

January 1982

**analog switch  
& IC product  
data book**















# Siliconix Analog Switch & IC Product Data Book

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# Siliconix Analog Switch & IC Product Data Book January 1982

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# About This Edition of the Siliconix Integrated Circuit Catalog

This Data Manual combines three previous publications: The Analog Switch, LSI and Telecommunications Data Books.

For Integrated Circuit Cross Referencing and Substitution, see the current issues of the Siliconix Short Form or OEM Pricing Guides.

## NEW PRODUCT DATA SHEETS APPEARING FOR THE FIRST TIME

D169	Dual Level Shifter Driver
DF328	Loop Disconnect Dialer, Push Button Activated
DG200A	PLUS-40 CMOS Dual SPST Analog Switch
DG201A	PLUS-40 CMOS Quad SPST Analog Switch
DG202	PLUS-40 CMOS Quad SPST Analog Switch
DG212	PLUS-40 CMOS Quad SPST Analog Switch
DG243	PLUS-40 CMOS Dual SPDT Analog Switch
DG300A-DG307A	PLUS-40 CMOS Family of Analog Switches
DG381A-DG390A	PLUS-40 CMOS Family of Analog Switches
DG309	PLUS-40 CMOS Quad SPST Analog Switch
DG5040-DG5045	PLUS-40 CMOS Family of Analog Switches
DG506A/DG507A	PLUS-40 CMOS 16-Channel Analog Multiplexer
DG508A/DG509A	PLUS-40 CMOS 8-Channel Analog Multiplexer
DG528/DG529	PLUS-40 CMOS 8-Channel Latchable Analog Multiplexer
Si1525/27B, Si2525/27B, Si3525/27B	Regulating Pulse Width Modulators

## DATA SHEETS NO LONGER INCLUDED

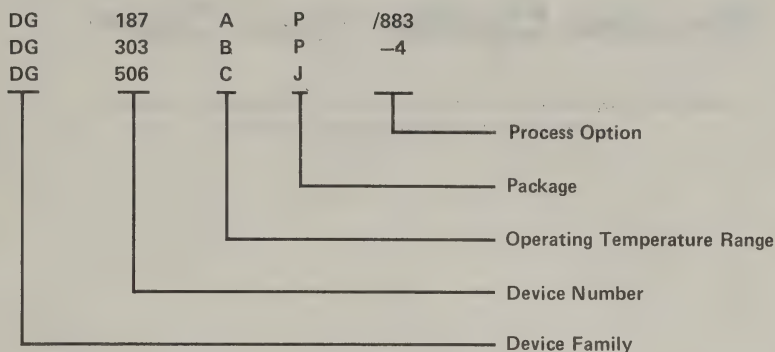
DGM111	Dual PMOS SPST Switch — Note 1
DGM122	Dual PMOS DPST Switch — Note 1
DF331A/DF332A/DF334A	$\mu$ -Law Companding CODEC — Note 1
DF341/DF342	A-Law Companding CODEC — Note 1
LD111/LD114	3½-Digit Serial Output A/D Converter Set — Note 2
LD130	3-Digit Integrating A/D Converter — Note 2
SM310	SMOKE Detector Battery Operated, Piezo Horn Drive — Note 1

Notes: 1. Contact factory on availability.  
2. Obsolete product.





# Device Ordering Information



## DEVICE FAMILY (1, 2 or 3 Letters)

- D** — Drivers for FET Switches
- DF** — Digital Function
- DG** — Analog Switches
- DGM** — Analog Switches
- G** — Multi-Channel FETs
- L** — Linear
- LD** — Linear Digital Combinations
- Si** — Siliconix Second Source Part
- SJM** — QPL Listed Part

## PACKAGE (1 Letter)

- A** — Metal Can
- J** — Dual In-Line Package — Plastic
- K** — Dual In-Line Package — CERDIP
- L** — Flat Package
- P** — Dual In-Line Package — Side Braze
- R** — Dual In-Line Package — Side Braze

## DEVICE NUMBER (3 or 4 Digit Numbers)

## OPERATING TEMPERATURE RANGE (1 Letter)

- A** — -55 to 125°C
- B** — -20 to 85°C
- C** — 0 to 70°C
- D** — -40 to 85°C (Applies to Telecom Products only)

B temperature range parts receive industrial processing unless a process option dash number is added to the part number.

C and D temperature range parts are given commercial processing.

All possible combinations of device types, temperature ranges, package types and MIL-883 process options are not necessarily available. Consult individual data book pages for complete information, or sales office.

## PROCESS OPTION

- /883** MIL-STD-883, Class B
- 4** 160 Hour Burn-In
- BS9000** Series

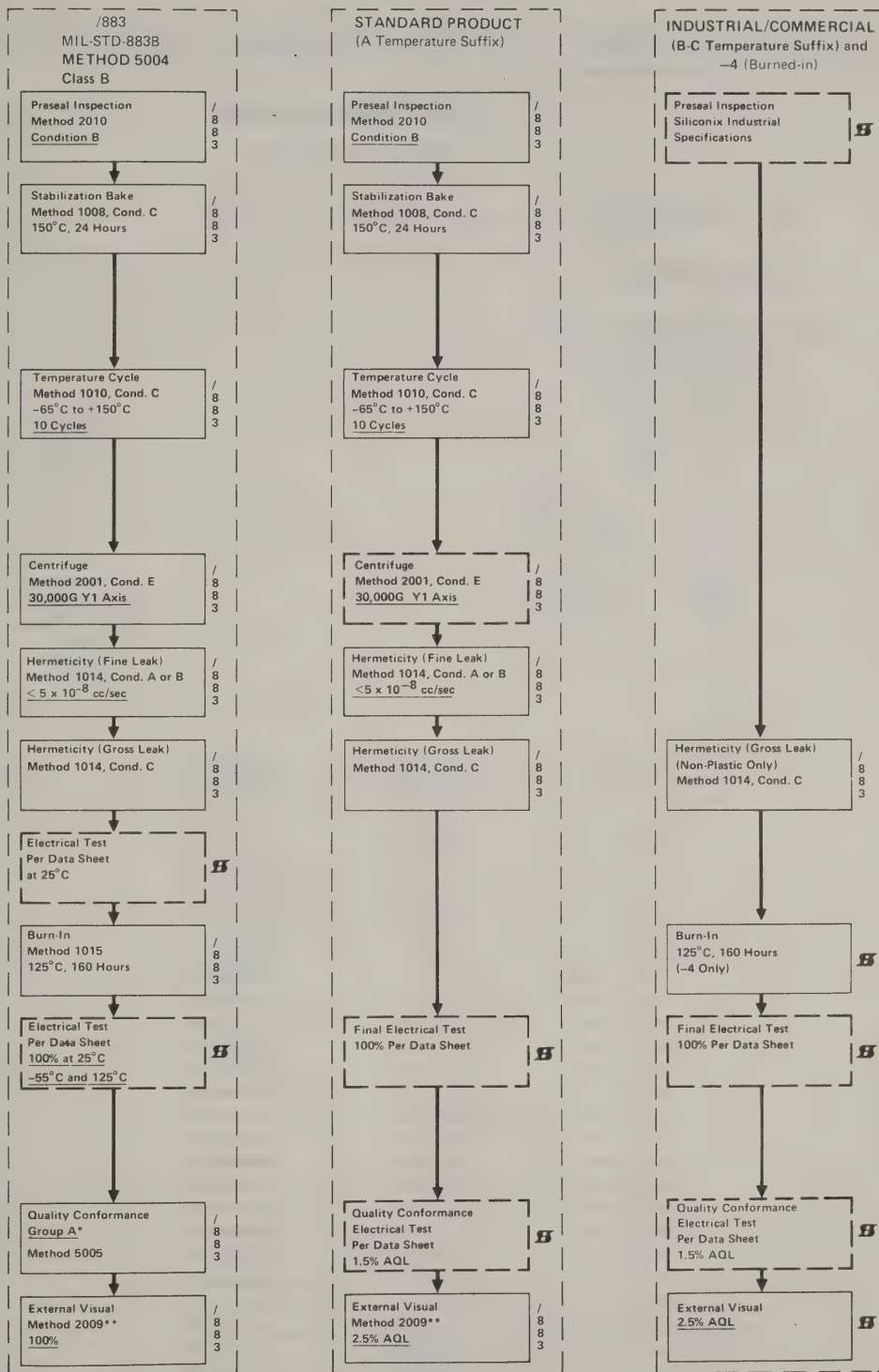
## Process Option Flow Chart

The Process Option Flow Chart shows the standard screening options provided by Siliconix for Integrated Circuits.

- Column 1:** Denotes the screening process for MIL-883, Class B. To order a part screened to this option, add a "/883" following the package suffix letter. If Group B or C Quality Conformance is also required, call out as a separate line item. Parts in this classification are carried in inventory.
- Column 2:** Is the screening procedure for military grade standard products ("A" temperature suffix).
- Column 3:** Is the normal screening procedure for industrial and commercial grade products (B and C temperature suffixes). An industrial and commercial grade product (B and C temperature range) may be given a 160 hour burn-in at 125°C by adding a Dash 4 (-4) following the package suffix letter.



# Process Option Flow Chart



\*Group B and C tests done to customer order on /883 parts

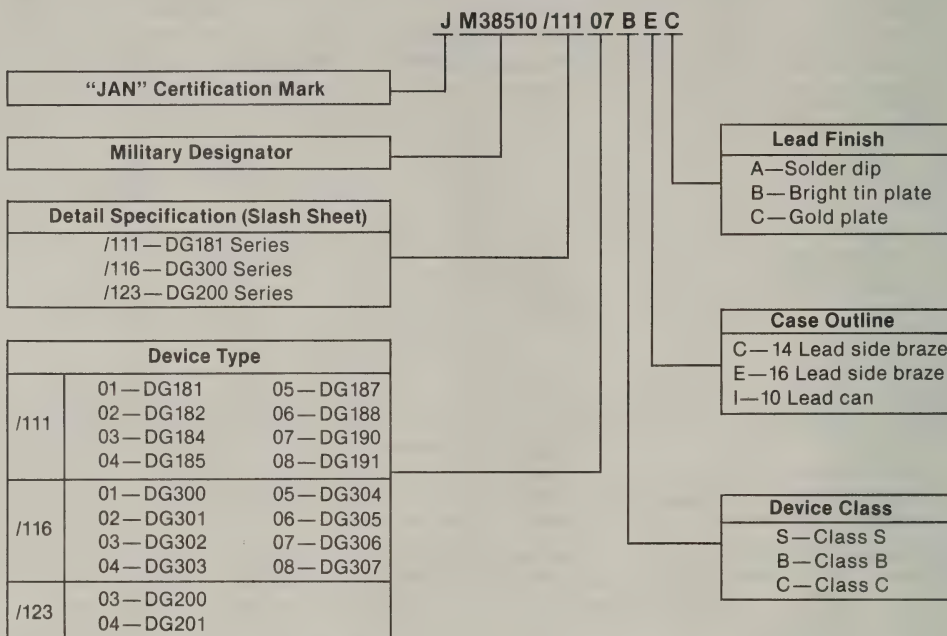
\*\*Physical Dimensions Excluded

The latest revision of MIL-STD-883 is applicable

# JAN 38510 Analog Switches

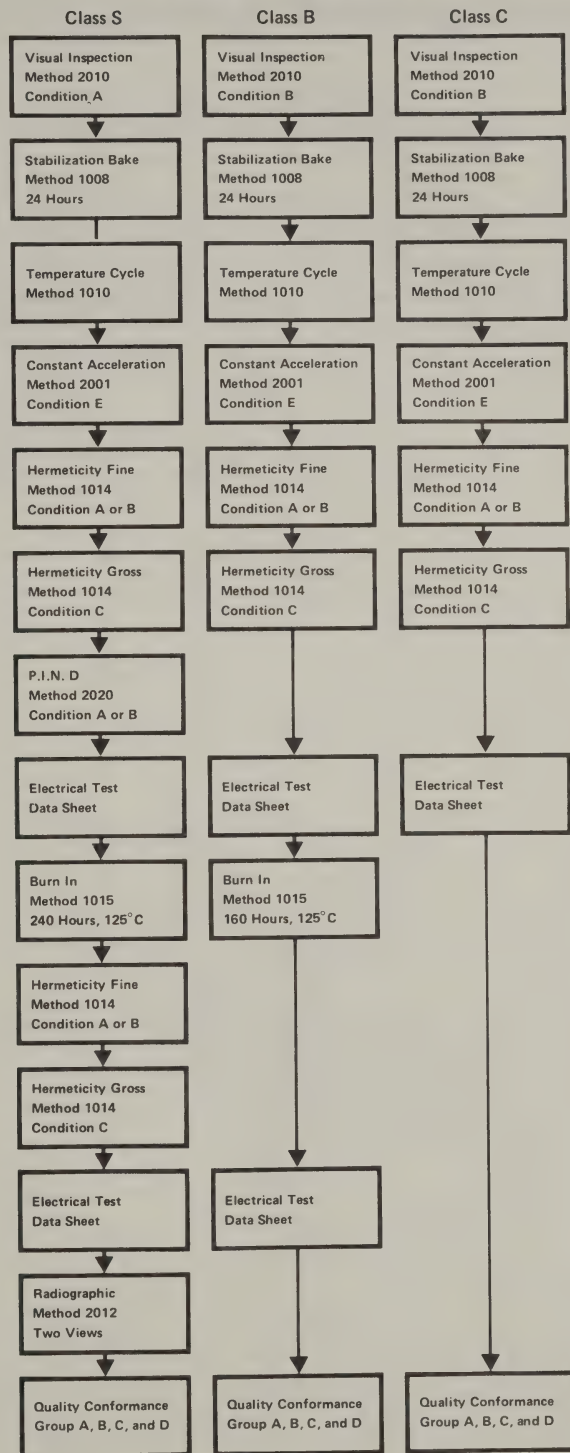
"Several Siliconix Analog Switches are available fully certified on the QPL (Qualified Parts List) published monthly by Defense Electronics Supply Center (DESC). The QPL numbers follow this format JM38510/XXXX. Refer to the current Siliconix Price List for available part types and order numbers."

## JAN Part Numbering System



Part Number	Order Part Number	Generic Part Number
JM38510/11101BCC	SJM181BCC	DG181AP/883
JM38510/11101BIC	SJM181BIC	DG181AA/883
JM38510/11102BCC	SJM182BCC	DG182AP/883
JM38510/11102BIC	SJM182BIC	DG182AA/883
JM38510/11103BEC	SJM184BEC	DG184AP/883
JM38510/11104BEC	SJM185BEC	DG185AP/883
JM38510/11105BCC	SJM187BCC	DG187AP/883
JM38510/11105BIC	SJM187BIC	DG187AA/883
JM38510/11106BCC	SJM188BCC	DG188AP/883
JM38510/11106BIC	SJM188BIC	DG188AA/883
JM38510/11107BEC	SJM190BEC	DG190AP/883
JM38510/11108BEC	SJM191BEC	DG191AP/883
JM38510/11601BCC	SJM300BCC	DG300AP/883
JM38510/11601BIC	SJM300BIC	DG300AA/883
JM38510/11602BCC	SJM301BCC	DG301AP/883
JM38510/11602BIC	SJM301BIC	DG301AA/883
JM38510/11603BCC	SJM302BCC	DG302AP/883
JM38510/11604BCC	SJM303BCC	DG303AP/883
JM38510/11605BCC	SJM304BCC	DG304AP/883
JM38510/11605BIC	SJM304BIC	DG304AA/883
JM38510/11606BCC	SJM305BCC	DG305AP/883
JM38510/11606BIC	SJM305BIC	DG305AA/883
JM38510/11607BCC	SJM306BCC	DG306AP/883
JM38510/11608BCC	SJM307BCC	DG307AP/883
JM38510/12303BCC	SJM200BCC	DG200AP/883
JM38510/12303BIC	SJM200BIC	DG200AA/883
JM38510/12304BEC	SJM201BEC	DG201AP/883

# JM38510/883 Process Option Flow Chart







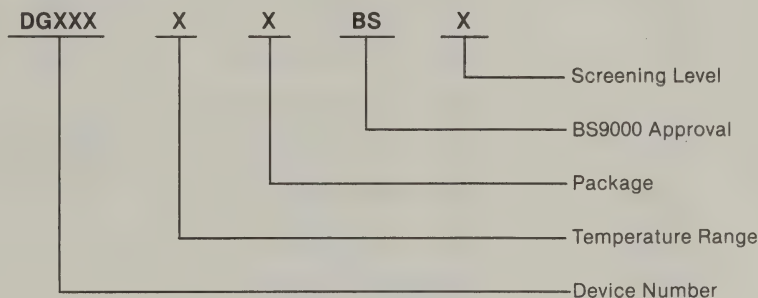
# BS9000 Approved Analog Switches

Siliconix is the first company to receive BS9000 approval for Analog Switch Devices. The advantages of such approval are:

- A controlled inspection is known to the customer, so reduces the customer's needs for Goods Inwards Inspection
- A more consistent quality of product
- Easier interchangeability of suppliers
- A product of known quality levels with, in general, a minimal increase in costs

It is the policy of the UK government to encourage the growth of the BS9000 scheme for the benefit of both government and industry. All the Siliconix BS9000-Approved parts are included in the British Ministry of Defence Preferred Range defined in DEF-STAN 56/36 and as such are first choice components for use in UK defense equipment. Under STANAG 4093 they carry approved status with other NATO member nations.

## Interpretation of Ordering Information



### Key

#### Temperature Range

- A -55°C to 125°C
- B -20°C to 85°C

#### Package

- A Metal Can
- L Flatpack
- P, R Dual-In-Line

#### Screening Level

- (Blank) Full Assessment
- .S1 Screening Level S1
- S2 Screening Level S2
- S3 Screening Level S3
- S4 Screening Level S4

# BS9000 Approved Analog Switches (Cont'd)

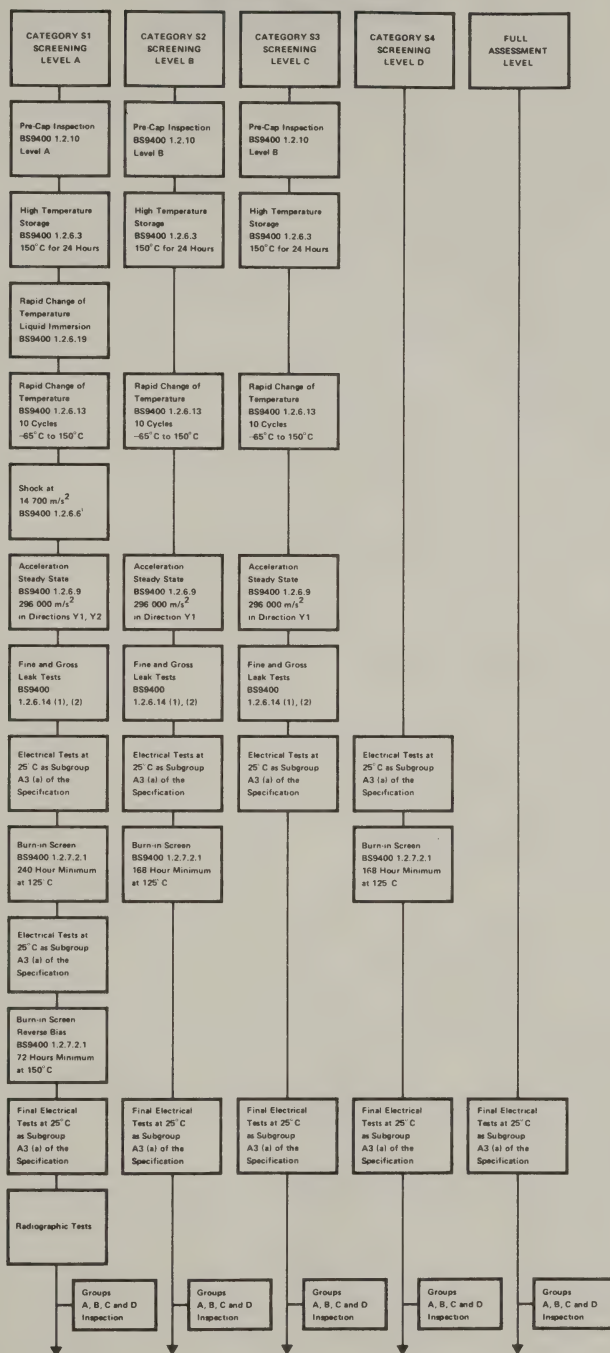
DEVICE PART NUMBER	BS DETAIL SPECIFICATION	Awaiting Approval*
		<b>Generic Part No.</b>
DG126	9491-F-0814 to 9491-F-0831	
DG129	9491-F-0832 to 9491-F-0849	DG281/ /BS
DG133	9491-F-0850 to 9491-F-0867	DG284/ /BS
DG134	9491-F-0868 to 9491-F-0885	DG287/ /BS
DG139	9491-F-0886 to 9491-F-0903	DG290/ /BS
DG140	9491-F-1030 to 9491-F-1038	DG300/ /BS
DG141	9491-F-1039 to 9491-F-1056	DG301/ /BS
DG142	9491-F-0904 to 9491-F-0921	DG302/ /BS
DG143	9491-F-0922 to 9491-F-0939	DG303/ /BS
DG144	9491-F-0940 to 9491-F-0957	DG304/ /BS
DG145	9491-F-1084 to 9491-F-1092	DG305/ /BS
DG146	9491-F-1093 to 9491-F-1110	DG306/ /BS
DG151	9491-F-1057 to 9491-F-1074	DG307/ /BS
DG152	9491-F-0958 to 9491-F-0975	DG381/ /BS
DG153	9491-F-1075 to 9491-F-1083	DG384/ /BS
DG154	9491-F-0976 to 9491-F-0993	DG387/ /BS
DG161	9491-F-1111 to 9491-F-1128	DG390/ /BS
DG162	9491-F-0994 to 9491-F-1011	
DG163	9491-F-1129 to 9491-F-1137	
DG164	9491-F-1012 to 9491-F-1029	
DG180	9491-F-0688 to 9491-F-0714	
DG181	9491-F-0508 to 9491-F-0534	
DG182	9491-F-0535 to 9491-F-0561	
DG183	9491-F-0733 to 9491-F-0750	
DG184	9491-F-0562 to 9491-F-0579	
DG185	9491-F-0580 to 9491-F-0597	
DG186	9491-F-0751 to 9491-F-0777	
DG187	9491-F-0598 to 9491-F-0624	
DG188	9491-F-0625 to 9491-F-0651	
DG189	9491-F-0715 to 9491-F-0732	
DG190	9491-F-0652 to 9491-F-0669	
DG191	9491-F-0670 to 9491-F-0687	
DG200	9491-F-0778 to 9491-F-0804	
DG201	9491-F-0805 to 9491-F-0813	
DG501	9491-F-1138 to 9491-F-1146	
DG503	9491-F-1147 to 9491-F-1155	
DG506	9491-F-1165 to 9491-F-1173	
DG507	9491-F-1174 to 9491-F-1182	
DG508	9491-F-1183 to 9491-F-1191	
DG509	9491-F-1192 to 9491-F-1200	
SI3705	9491-F-1156 to 9491-F-1164	

\*Contact one of the  
Siliconix Sales Offices  
for latest information.

Specifications are being raised for additional parts to BS9000, which will be qualified during the currency of this catalogue. For approval status and copies of the detail specifications for the products approved (or in course of qualification approval) please contact Siliconix Ltd., Morriston, Swansea SA6 6NE. Telephone (0792) 74681, Telex: 48197.



# BS9000 Series Process Option Flow Chart



**INSPECTION REQUIREMENTS:** All tests to be conducted at  $T_{amb} = 25^{\circ}\text{C}$  unless otherwise specified. Samples submitted to tests marked 'D' shall not be accepted for release under BS9000 (see 2.6.5 of BS9000 Part I).

Flow chart for 100% screening test procedures (see also Inspection Requirements). Production batches containing greater than 10% defective units subsequent to Burn-in will not be issued for release. The following acceptance/rejection criteria apply to electrical tests after Burn-in for screening levels A, B and D.

(a) Lots exhibiting greater than 20% defectives shall be rejected.

(b) Lots exhibiting less than 10% defectives shall be accepted.

(c) Lots exhibiting between 10% and 20% defectives (inclusive) shall have the defectives removed and the remainder of the lot subjected to an identical Burn-in. If such a Lot then exhibits greater than 5% defectives it shall be rejected.

**Radiographic tests.** Each device shall be examined, for extraneous matter and assembly defects, in the X and Y directions.





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## INTERFACE

### DECODERS/DISPLAY DRIVERS

Title		Page
DF412	Decodes Four Digit Multiplexed BCD to LCD Display Driver/Decodes up to 4 digits of multiplexed BCD information and derives the AC signals needed to drive a 4 digit LCD display. Any digit can be blanked as required.	1-1

### LEVEL SHIFTERS

	Channels	Input Load	Output Drive	t <sub>ON</sub> /t <sub>OFF</sub>	
D123	6	1 mA/1 $\mu$ A 1.0 V/0.4 V	ON—5 mA Sink, OFF—Block 30 V	500/1500 ns	1-8
D125	6	−0.7 mA/ +1 $\mu$ A 0 V/4.6 V	ON—5 mA Sink, OFF—Block 30 V	500/1500 ns	1-10
D129	4	−0.2 mA/ +.25 $\mu$ A 0 V/5 V	ON—10 mA Sink, OFF—Block 50 V	300/1500ns	1-12
D139	2	−500 $\mu$ A/ +10 $\mu$ A 0 V/ +5 V	30 V p-p @ 10 mA	170/200 ns	1-14
D169	2	−100 $\mu$ A/ +5 $\mu$ A 0 V/ +3 V	33 V p-p @ 40 mA	70-110 ns	1-20

*Stresses listed under "Absolute Maximum Ratings" may be applied (one at a time) to devices without resulting in permanent damage. This is a stress rating only and not subject to production testing. Exposure to absolute maximum rating conditions for extended periods may effect device reliability.*

# Four Digit LCD Decoder Driver

designed for . . .



DF412

## ■ Driving Liquid Crystal Displays Directly

### BENEFITS

- Reduces Complexity of Driving LCD Displays
- Blanking of any Digit with Input Code of 1111
- Only 1 Package Required to Drive Up to a 4 Digit Display
- Minimal Power Consumption
  - Typically 1.5 mW
  - Operates over 3.5 to 6.0 V supply
- Interfaces Readily with Most Logic Families
- No External Oscillator Required
- No Display Buffering Required
- Easy Multiple Driver Interfacing
- Eliminates DC Bias Levels That Degrade Display Lifetime

### DESCRIPTION

The DF412 Four Digit LCD Decoder Driver is a CMOS Monolithic device employing multiplexed BCD to LCD Decoding. A single DF412 contains all of the circuitry needed to decode up to 4 digits of multiplexed BCD information and derive the AC signals needed to directly drive a 4 digit LCD display. Included is the decoding of BCD input 1111 to blank a digit.

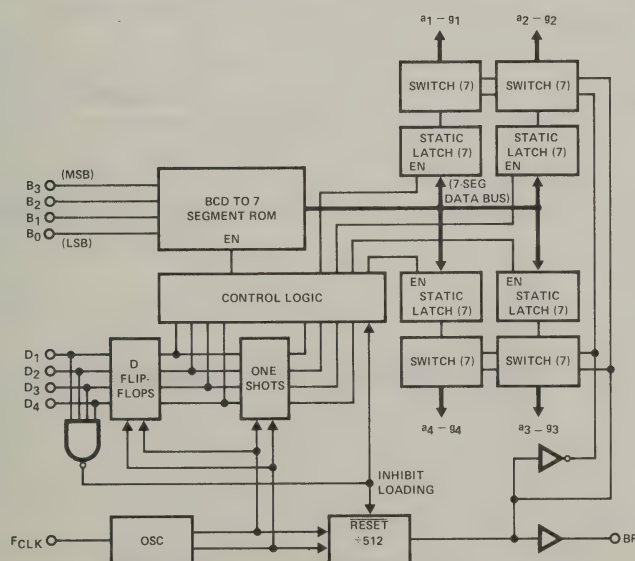
An internal oscillator, its frequency being controlled by an external capacitor, develops a backplane (BP) signal that is a square wave swinging between ground ( $V_{SS}$ ) and the positive supply ( $V_{DD}$ ). Segment drivers supply square waves of the same frequency as the backplane but either in phase for an OFF segment or out of phase for an ON segment. In this manner of LCD digit driving the net DC potential applied between segment and backplane is zero, a necessary requirement for long display life. Digital input levels are defined as input voltages  $> 4$  V being a logic "1" and input voltages  $< 0.8$  V being a logic "0" with  $V_{DD} = 5$  V.

BCD input data is decoded into 7 segment form using an on board ROM. The 7 segment data is then latched into the appropriate static latches via the digit strobe inputs and control logic.

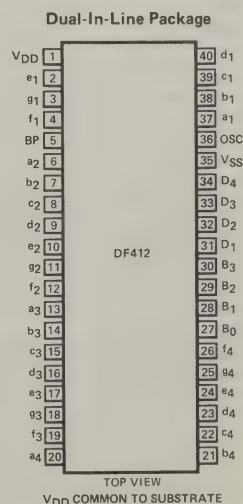
The pinout of the DF412 allows easy PC board interfaces to Dual-In-Line LCDs as well as edge connecting types of displays.

Interface

### FUNCTIONAL BLOCK DIAGRAM



### PIN CONFIGURATION



ORDER NUMBER DF412CJ  
SEE PACKAGE 22

## ABSOLUTE MAXIMUM RATINGS

$V_{DD} - V_{SS}$  . . . . . -0.3 V to 8 V  
Voltage on Any Pin . . . . .  $V_{SS} - 0.3$  V to  $V_{DD} + 0.3$  V  
Current at Any Pin . . . . . 10 mA  
Operating Temperature . . . . . 0 to 70°C

Storage Temperature . . . . . -65 to 125°C  
Power Dissipation (Package)\* . . . . . 450 mW  
\*Device mounted with all leads welded or soldered to PC board.  
Derate 6.3 mW/°C above 25°C.

## ELECTRICAL CHARACTERISTICS

All DC parameters are 100% tested at 25°C. Lots are sample tested for AC parameters to assure conformance with specifications.

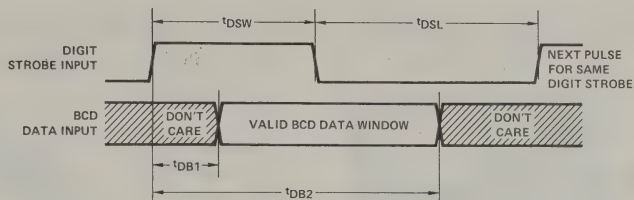
Characteristic				Limits			Unit	Test Conditions $V_{DD} = 5$ V, $T_A = 25^\circ\text{C}$ $V_{SS} = 0$ V, $C_{OSC} = 200$ pF
				Min	Typ <sup>1</sup>	Max		
1	INPUTS	$I_{IN}$ (Digits)	Digital Inputs		0.01	1	$\mu\text{A}$	$V_{IN} = 5$ V
2		$I_{IN}$ (FCLK)	Oscillator Input		350			$V_{IN} = 0$ V
3		$V_{INL}$	Digital Inputs			0.8	V	BCD and DS Inputs
4			Logic Low Voltage			0.5		Clock Input
5		$V_{INH}$	Digital Inputs	4.0				BCD and DS Inputs
6			Logic High Voltage	4.5				Clock Input
7	OUTPUTS	$V_{OL}$ (Segments)	Segment Output		0.3	0.7	V	$I_{OL} = 250 \mu\text{A}$
8			Voltage in "0" State		0.03			$I_{OL} = 25 \mu\text{A}$
9		$V_{OH}$ (Segments)	Segment Output	4.3	4.7			$I_{OH} = -250 \mu\text{A}$
10			Voltage in "1" State		4.97			$I_{OH} = -25 \mu\text{A}$
11		$V_{OL}$ (Backplane)	Backplane Output		0.3	0.7		$I_{OL} = 5$ mA
12			Voltage in "0" State		0.03			$I_{OL} = 0.5$ mA
13		$V_{OH}$ (Backplane)	Backplane Output	4.3	4.7			$I_{OH} = -5$ mA
14			Voltage in "1" State		4.97			$I_{OH} = -0.5$ mA
15	DYNAMIC	$t_r$ (Segments)	Segment Output		1.0		$\mu\text{s}$	$C_{LOAD} = 200$ pF
16		$t_f$ (Segments)	Segment Output		1.0			
17		$t_r$ (Backplane)	Backplane Output		0.8			$C_{LOAD} = 3900$ pF
18		$t_f$ (Backplane)	Backplane Output		0.8			
19		F <sub>BP1</sub>	Backplane Frequency	Min LCD	30		Hz	$C_{OSC} = 3800$ pF
20		F <sub>BP2</sub>		Max LCD	100			$C_{OSC} = 1000$ pF
21	SUPPLY	$I_{DD}$ (Digital Inputs Static)	Supply Current		140	400	$\mu\text{A}$	See Figure 2
22		$I_{DD}$ (Digital Inputs Dynamic)	Supply Current		155			See Figure 3
23		$V_{DD}$ Range	Operating Supply Voltage Note 2	3.5	5	6	V	

## NOTES:

- Typical values are for Design Aid Only, and are not guaranteed nor subject to production testing.
- Operation over the supply voltage range is functionally tested. DC and AC parametric testing is performed only at specified test conditions.



B <sub>3</sub>	B <sub>2</sub>	B <sub>1</sub>	B <sub>0</sub>	DISPLAY CHARACTER
0	0	0	0	0
0	0	0	1	1
0	0	1	0	2
0	0	1	1	3
0	1	0	0	4
0	1	0	1	5
0	1	1	0	6
0	1	1	1	7
1	0	0	0	8
1	0	0	1	9
1	0	1	0	A
1	0	1	1	B
1	1	0	0	C
1	1	0	1	D
1	1	1	0	E
1	1	1	1	BLANK



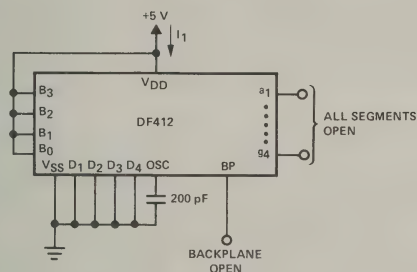
Recommended Drive Conditions*		Min	Max
$t_{CP}$	Clock Period	19.5 $\mu s^{**}$	65 $\mu s^{**}$
$t_{DSW}$	Digit Strobe Pulse Width	$t_{CP} + 1 \mu s$	—
$t_{DSL}$	Digit Strobe Low Time	2 $t_{CP}$	—
$t_{DB1}$	Digit Strobe to BCD Setup Time	— $\infty$	$t_{CP} - 2 \mu s$
$t_{DB2}$	Digit Strobe to BCD Hold Time	2 $t_{CP} + 2 \mu s$	$\infty$

\*These minimum/maximum conditions indicate the necessary conditions to insure operation. They are based on design structure (shown in Figure 8a) with sufficient guardband to allow for propagation delay changes. *They are not tested nor guaranteed.*

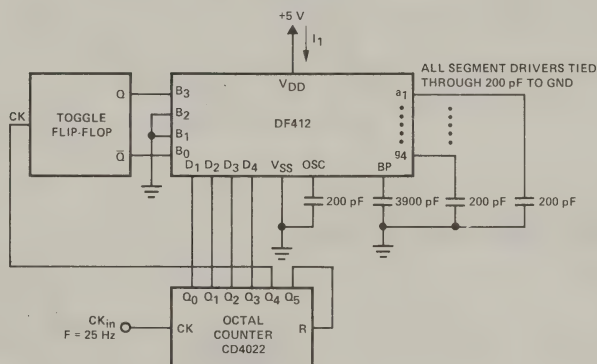
\*\*The min-max clock periods correspond to a 30 Hz–100 Hz LCD backplane frequency range.

Figure 1

## TEST CIRCUITS



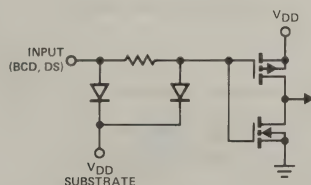
Static Supply Current Test Setup  
Figure 2



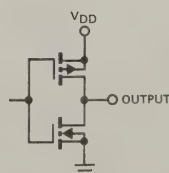
Dynamic Supply Current Test Setup  
Figure 3

## INPUT-OUTPUT SCHEMATICS

Input Structure



Output Structure



## TYPICAL CHARACTERISTICS

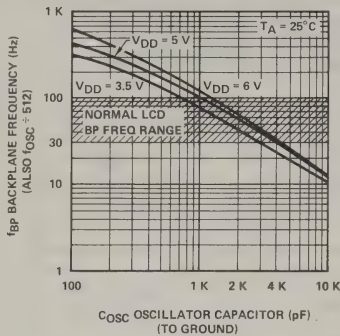
Backplane Frequency Vs.  
COSC Vs. VDD

Figure 4

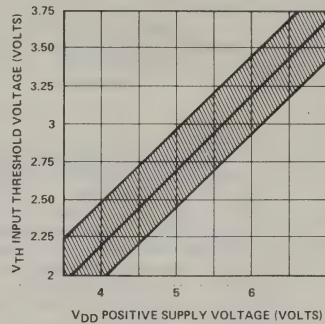
Input Threshold Vs.  
Positive Supply Voltage

Figure 5

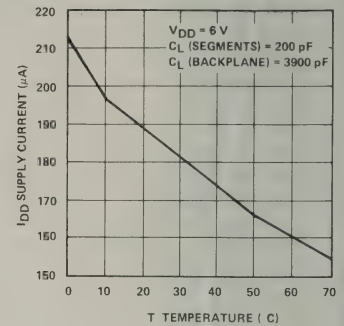
Supply Current Vs.  
Temperature

Figure 6

## TYPICAL WAVEFORMS

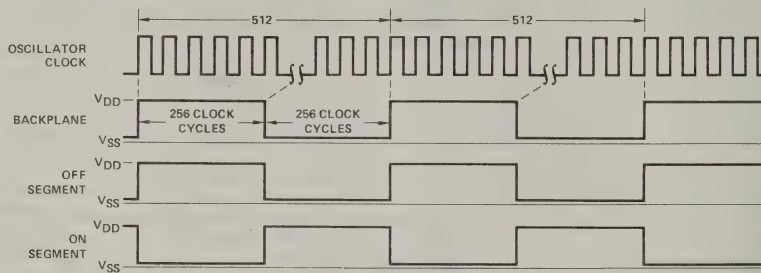
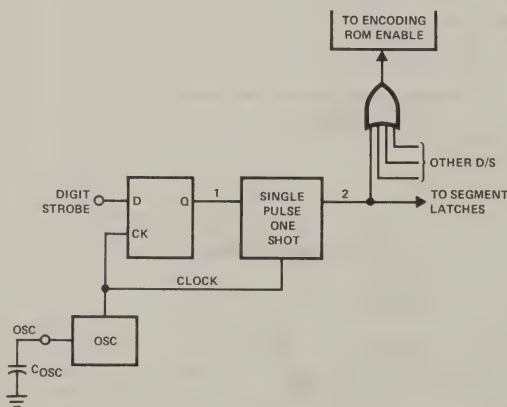
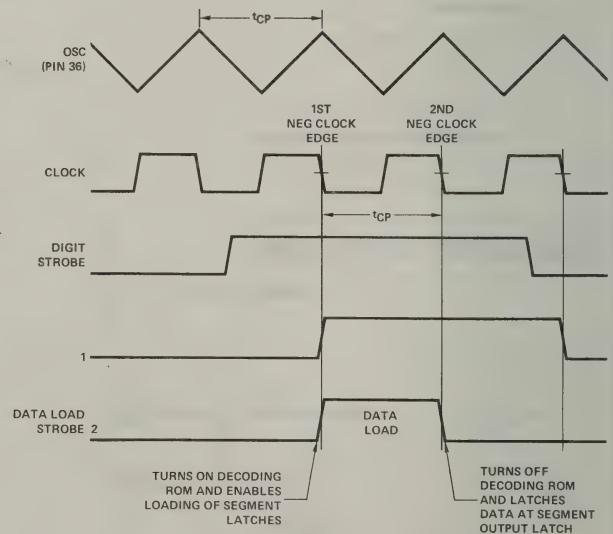


Figure 7

## DIGIT STROBE INPUT STAGE

Digit Strobe Input Circuit  
Figure 8aDigit Strobe and Clock Timing  
Relationships to Data Loading  
Figure 8b

## PIN DESCRIPTIONS

**Oscillator** — A capacitor connected between the oscillator pin and ground completes the integral clock generator. The frequency of the clock generator ( $f_{OSC}$ ) is determined by the capacitance value and the  $V_{DD}$  voltage, as seen in Figure 4. For driving LCDs with a 30 Hz to 100 Hz backplane frequency range, the typical oscillator capacitor is 1000 pF to 3800 pF (for  $V_{DD} = 5$  V). The oscillator pin can also be driven with an external clock whose output swings within 10% of  $V_{DD}$  and  $V_{SS}$ . This is useful when synchronization of more than one DF412 is necessary, such as when driving displays of more than 4 digits on a single backplane.

**Backplane** — The backplane of the liquid crystal display is driven by this pin whose output is a squarewave swinging between  $V_{DD}$  and  $V_{SS}$ . The frequency of the backplane signal is  $f_{OSC}/512$ . Most LCDs require backplane frequencies of between 30 Hz and 100 Hz. See Figure 4 for a graph of oscillator capacitance vs backplane frequency.

**Digit Strokes  $D_1$ – $D_4$  and BCD Inputs  $B_3$ ,  $B_2$ ,  $B_1$  and  $B_0$** — Multiplexed BCD information is entered into the DF412 by presenting the appropriate BCD code to the inputs  $B_3$ ,  $B_2$ ,  $B_1$  and  $B_0$  and by pulsing the appropriate digit stroke input  $D_1$ ,  $D_2$ ,  $D_3$  or  $D_4$  with positive true logic (i.e.,  $V_{INH} \geq [0.8 \times V_{DD}]$  for logic 1,  $V_{INL} \leq 0.8$  V for logic 0). The minimum pulse width of a digit stroke should be not less than one period of the oscillator frequency. Information presented at the BCD inputs ( $B_3$ ,  $B_2$ ,  $B_1$ ,  $B_0$ ) must be valid during the digit stroke pulse. See the timing requirements in Figure 1.

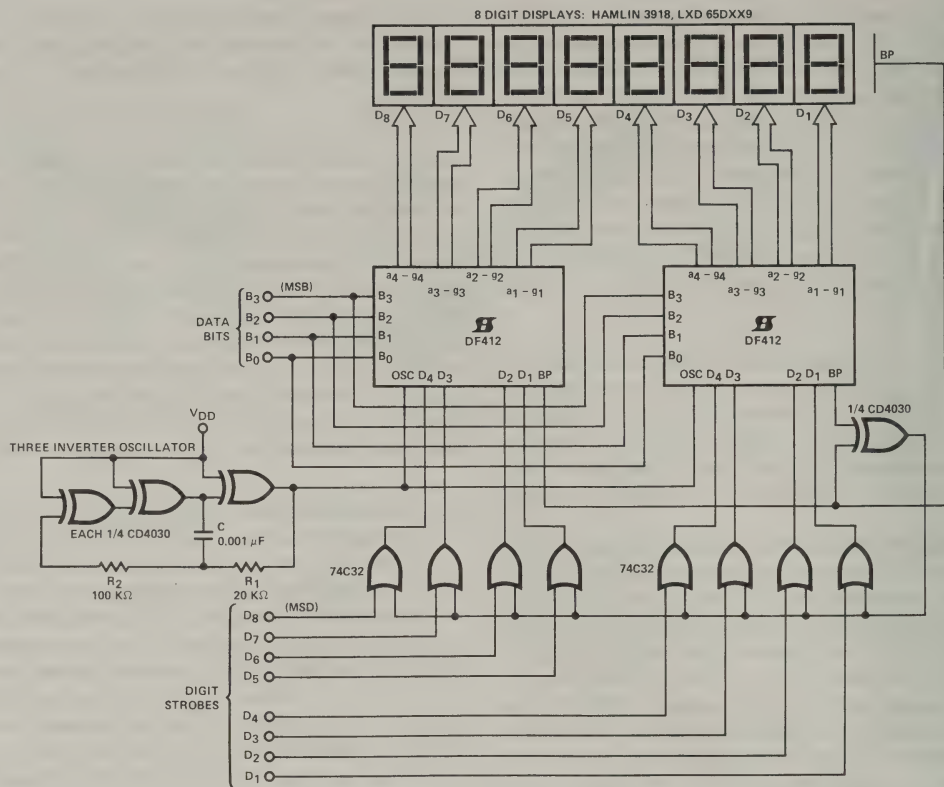
The digit stroke inputs are shaped by the input logic shown in Figure 8a. This logic causes a strobe signal which is a single clock period wide. The active time of this data load strobe (shown in Figure 8b) enables the BCD to 7-segment decoding ROM, which brings the new 7-segment data to the output latches. Delay time for data to get from BCD input to the segment outputs is typically 2  $\mu$ s–3  $\mu$ s. The end of the data load strobe is triggered by the second negative clock edge following the digit stroke going high. At this

edge, the segment outputs are latched, storing the 7-segment information for this digit. This input structure is the basis for the timing requirements of the DF412, shown in Figure 1.

The digit strobe input structure can actually load more than one digit at a time from the same BCD input. The loading of multiple digits can save time for microprocessor applications, such as for zeros, or blanks. However, all four digits cannot be simultaneously loaded due to a special decode of  $D_1 \cdot D_2 \cdot D_3 \cdot D_4$  which causes a reset of the backplane divider and inhibits loading of the BCD data. Unused Digit Strokes should be tied to ground, to avoid them floating to a logic 1 condition which could cause an inadvertent reset condition. The reset condition stops the backplane square wave, putting the DF412 drive in a steady voltage state which would degrade the LCD for long term application.

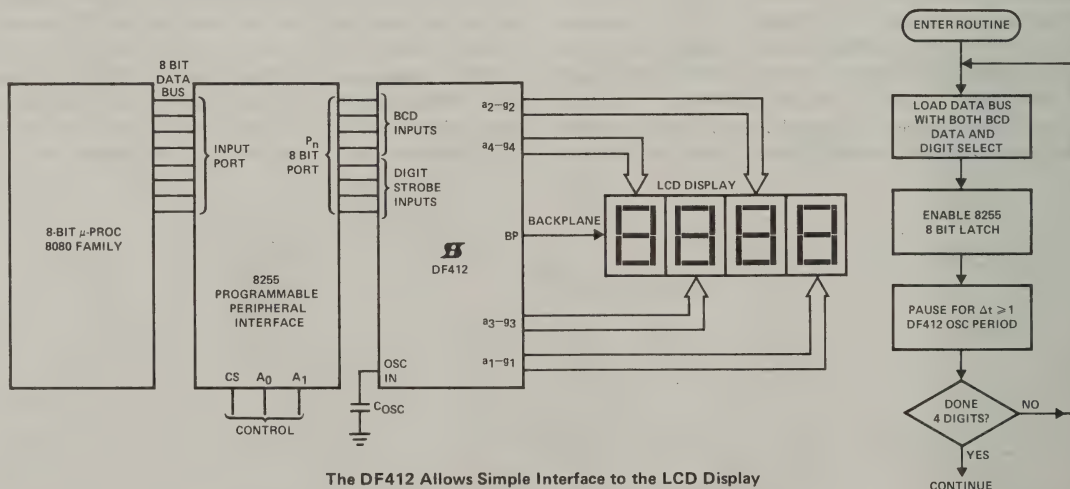
When ganging more than one DF412 together, it is necessary to synchronize the individual backplane signals to insure proper segment-backplane signal phase relationships. This is easily accomplished by initially pulling all digit stroke inputs high and by then driving the ganged DF412s with a common oscillator. By comparing the individual backplane signals of two DF412s with an exclusive or gate (see Figure 10) a continual checking of the backplane phase relationships can be accomplished. Should, for some reason, the individual backplane signals become out of phase an automatic reset will occur and proper phase once again will be established.

**Segment Outputs** — Segments are driven with the DF412 segment outputs which generate square waves which are either in phase with the backplane for an OFF segment or out of phase with the backplane for an ON segment. Output swings of the drivers are between  $V_{DD}$  and  $V_{SS}$ . Segment peak to peak voltages are then  $2X (V_{DD} - V_{SS})$ . The CMOS output drivers provide matched resistance to both  $V_{DD}$  and ground, eliminating any net DC voltage component on the LCD to give maximized display life.



Ganged DF412's Drive 8 Digit LCD

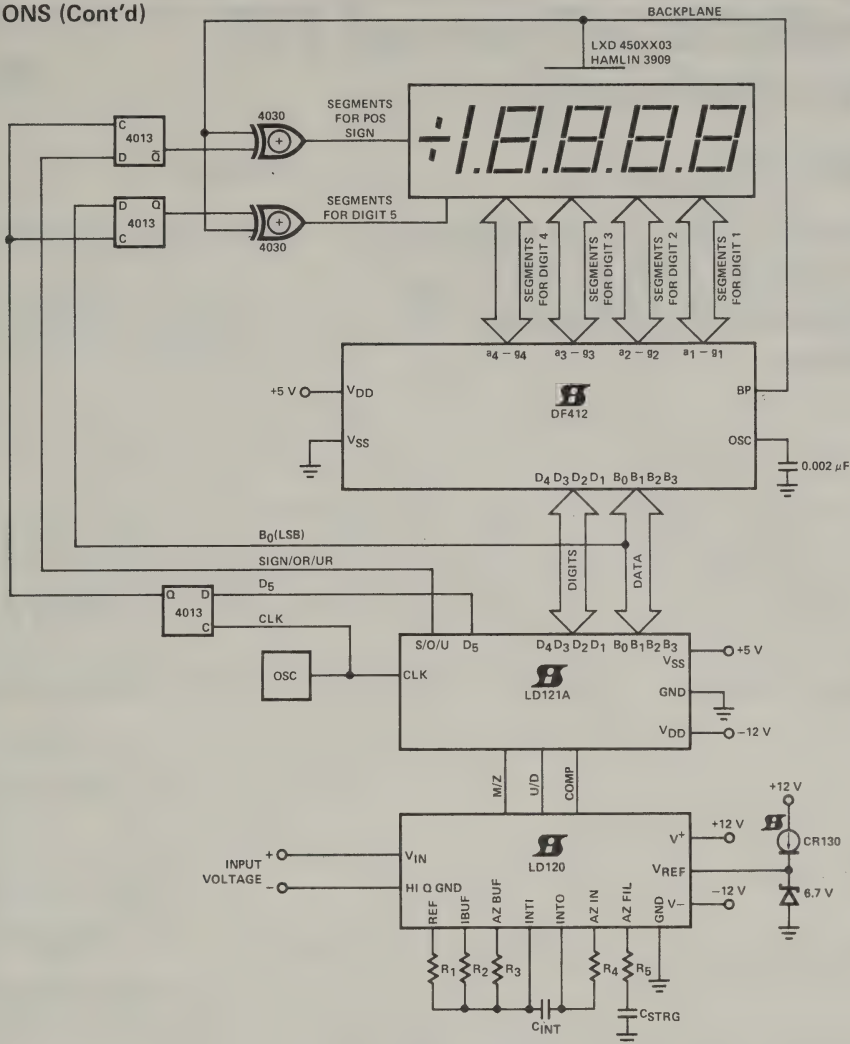
Figure 9



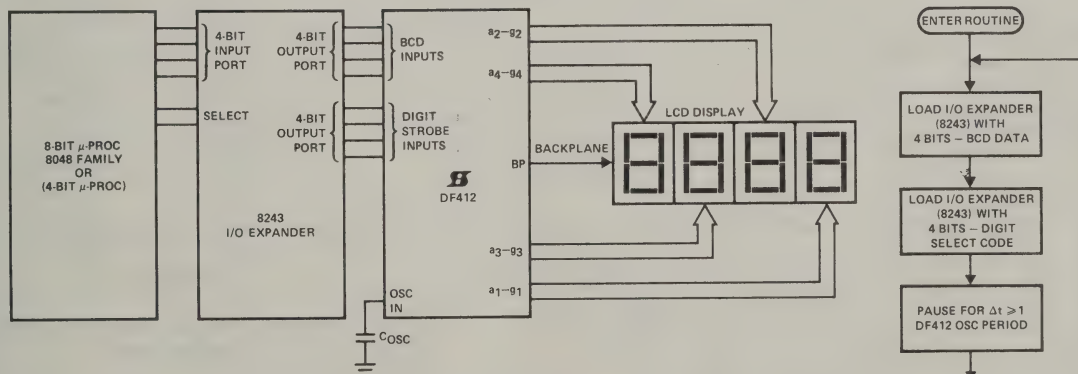
The DF412 Allows Simple Interface to the LCD Display from an 8080 Microprocessor. Data Transfer is Made with an 8 Bit Dump, Bringing Both the BCD Input and the Digit Strokes to the Chip in Parallel

Figure 10





4 1/2 Digit LCD-DVM  
Figure 11



Simple LCD Interface with 8048 Family of Microprocessors.  
Data Transfer is Made with Two 4-Bit Ports, Loaded  
with 4-Bit Dumps. Note in the Flow Chart that the BCD  
Data is Latched to the Expander First, then the Digit Strobe  
is Sent Out. This Insures Proper Data Being Loaded in.

Figure 12

# Monolithic 6-Channel FET Switch Drivers



*designed for . . .*

## ■ Interfacing Low Level Signals to FET Switches such as G115 and G122 Series Multi-Channel FET Switches

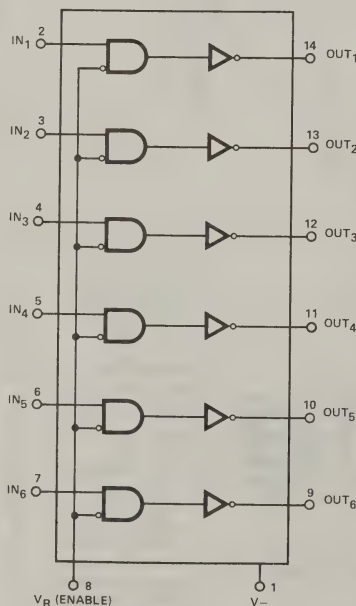
### BENEFITS

- Reduces System Component Requirements
  - Six Interface Circuits on One Chip
  - Performs Amplification and DC Level Shifting Required Between Low Level Logic and FET Switches

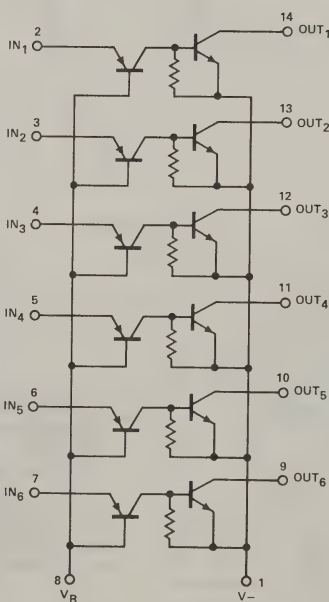
### DESCRIPTION

The D123 contains six drivers designed to perform the level-shifting and amplification needed to interface low-level logic outputs and field-effect transistor switches (MOS FET or JFET). With the input logic reference,  $V_R$ , at 0 V, the driver output reference,  $V_-$  may be set between  $-3$  and  $-30$  V. Each output is designed to sink 5 mA of current in the ON condition, and to hold off up to 30 V in the OFF condition. The input stage is a common-base emitter-input PNP transistor, and thus has a low input impedance. For the ON condition, an input current equal to or greater than 1 mA is required.

### FUNCTIONAL DIAGRAM

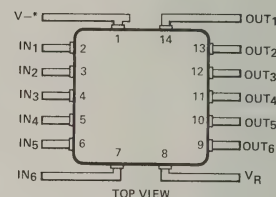


### SCHEMATIC DIAGRAM



### PIN CONFIGURATIONS

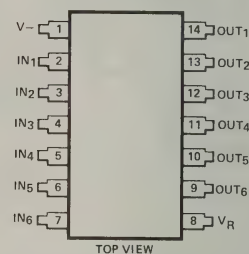
#### Flat Package



ORDER NUMBER: D123AL  
SEE PACKAGE 5

\*Common to Substrate and Base of Package.

#### Dual-In-Line Package



ORDER NUMBERS: D123AP OR D123BP  
SEE PACKAGE 11

## ABSOLUTE MAXIMUM RATINGS

$V_O$ to $V_-$	36 V
$V_R$ to $V_-$	25 V
$V_{IN}$ to $V_-$	30 V
$V_{IN}$ to $V_R$	$\pm 2$ V
Current (Any Terminal)	30 mA
Storage Temperature	-65 to 150°C

Operating Temperature (A Suffix) . . . . . -55 to 125°C  
 (B Suffix) . . . . . -20 to 85°C

## Power Dissipation\*

Flat Package**	750 mW
14 Pin DIP***	825 mW

\*All leads welded or soldered to PC board.

\*\*Derate 10 mW/°C above 75°C.

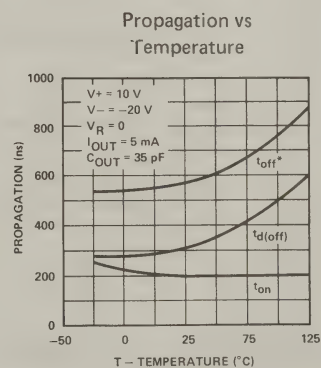
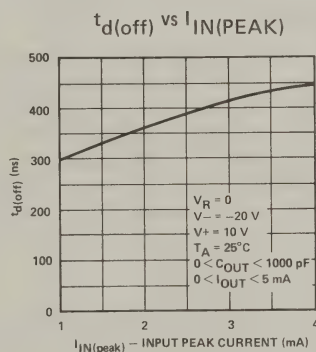
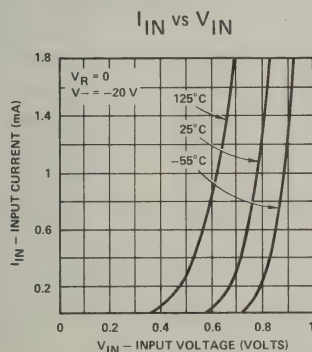
\*\*\*Derate 11 mW/°C above 75°C.

**ELECTRICAL CHARACTERISTICS** All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

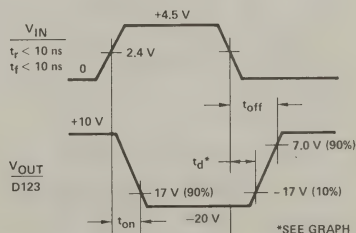
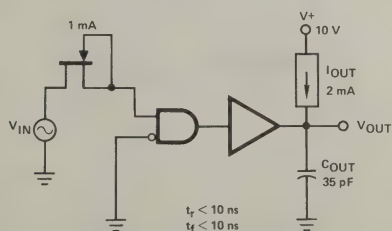
CHARACTERISTIC			MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V <sub>-</sub> = -20 V, V <sub>R</sub> = 0		
			D123A			D123B						
			-55°C	25°C	125°C	-20°C	25°C	85°C				
1	OUT	V <sub>OL</sub>	Output Voltage, Low	-19.6	-19.6	-19.5	-19.6	-19.6	-19.5	V	I <sub>O</sub> = 5 mA, I <sub>IN</sub> = 1 mA	
2		I <sub>OH</sub>	Output Current, High	0.1	0.1	10	0.1	0.1	10	μA	V <sub>O</sub> = 10 V, V <sub>IN</sub> = 0.4 V	
3	IN	I <sub>INL</sub>	Input Current, Input Voltage Low	1	1	100	1	1	100	μA	V <sub>IN</sub> = 0.4 V	
4		V <sub>INH</sub>	Input Voltage, High	1.3	1	0.8	1.3	1	1	V	I <sub>IN</sub> = 1 mA	
5	TIME	t <sub>on</sub>	Turn-ON Time		0.5			0.5		μs	See Switching Time Test Circuit	
6		t <sub>off</sub>	Turn-OFF Time		1.2			1.5				
7	SUPPLY	I <sub>-</sub>	Negative Supply Current	-1	-1	-1.5	-1	-1	-1.5	mA	I <sub>O</sub> = 0	I <sub>IN1</sub> = 1 mA, All Other V <sub>IN</sub> = 0.4 V
8		I <sub>R</sub>	Reference Supply Current	-0.5	-0.5	-0.5	-0.6	-0.6	-0.6			
9		I <sub>-</sub>	Negative Supply Current	-2	-2	-200	-5	-5	-100	μA	V <sub>O</sub> = 10 V	All V <sub>IN</sub> = 0.4 V
10	I <sub>R</sub>	Reference Supply Current	-1	-1	-150	-5	-5	-100				

IBAF-A

## TYPICAL CHARACTERISTICS



## SWITCHING TIME TEST CIRCUIT



\*SEE GRAPH

# Monolithic 6-Channel FET Switch Drivers



*designed for . . .*

## ■ Interfacing Low Level Signals to FET Switches such as G115 and G122 Series Multi-Channel FET Switches

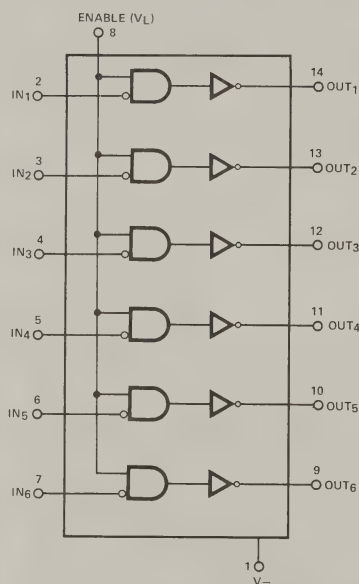
### BENEFITS

- Reduces System Component Requirements
  - Six Interface Circuits in One Chip
  - Performs Amplification and DC Level Shifting
- Required Between Low Level Logic and FET Switches

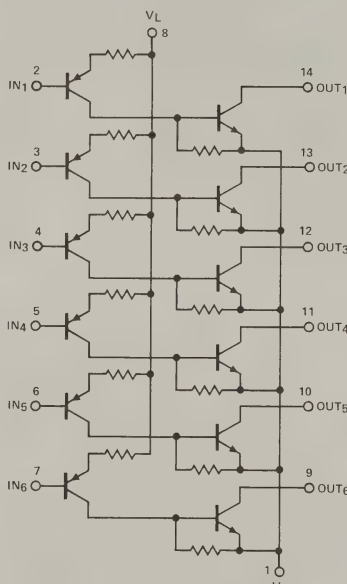
### DESCRIPTION

The D125 contains six drivers, designed to perform the level-shifting and amplification needed to interface low-level logic outputs and field-effect transistor switches (MOS FET or JFET). With the input logic supply,  $V_L$ , at 5 V, the driver output reference,  $V_-$  may be set between  $-1$  and  $-25$  V. Each output is designed to sink 5 mA of current in the ON condition, and to hold off up to 30 V in the OFF condition. The input stage is a base-input PNP transistor, with the emitter returned to the  $V_L$  supply through a resistor. To turn the driver ON, the logic stage driving it must be capable of sinking 0.7 mA.

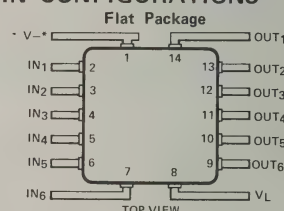
### FUNCTIONAL DIAGRAM



### SCHEMATIC DIAGRAM



### PIN CONFIGURATIONS



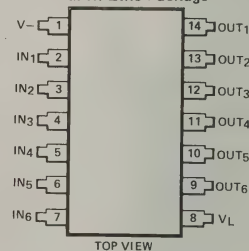
ORDER NUMBER:

D125AL

SEE PACKAGE 5

\*Common to Substrate and Base of Package

Dual-In-Line Package

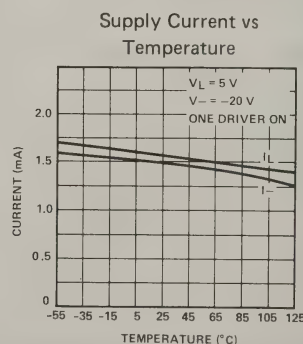
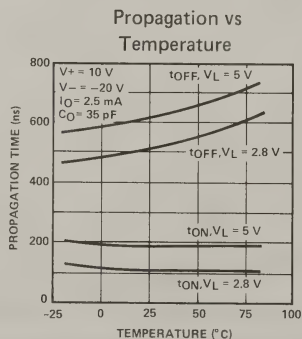


ORDER NUMBERS:

D125AP OR D125BP

SEE PACKAGE 11

### TYPICAL CHARACTERISTICS





## ABSOLUTE MAXIMUM RATINGS

$V_O$ to $V_-$ .....	36 V
$V_L$ to $V_-$ .....	30 V
$V_{IN}$ to $V_-$ .....	30 V
$V_{IN}$ to $V_L$ .....	$\pm 6$ V
Current (Any Terminal) .....	30 mA
Storage Temperature .....	-65 to 150°C
Operating Temperature (A Suffix) .....	-55 to 125°C
(B Suffix) .....	-20 to 85°C

## Power Dissipation\*

Flat Package** .....	750 mW
14 Pin DIP*** .....	825 mW

\*All leads welded or soldered to PC board.

\*\*Derate 10 mW/°C above 75°C.

\*\*\*Derate 11 mW/°C above 75°C

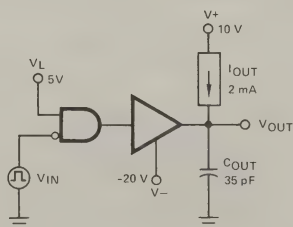
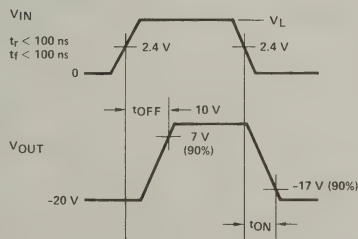
## ELECTRICAL CHARACTERISTICS

All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC			MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V <sub>-</sub> = -20 V, V <sub>L</sub> = 5 V		
			D125A			D125B						
			-55°C	25°C	125°C	-20°C	25°C	85°C				
1	OUT	V <sub>OL</sub>	Output Voltage, Low	-19.6	-19.6	-19.5	-19.6	-19.6	-19.5	V	I <sub>O</sub> = 5 mA, V <sub>L</sub> = 4.5 V, V <sub>IN</sub> = 0.5 V	
2		I <sub>OH</sub>	Output Current, High	0.1	0.1	10	0.1	0.1	10	μA	V <sub>O</sub> = 10 V, V <sub>IN</sub> = 4.6 V	
3	IN	I <sub>INH</sub>	Input Current, Input Voltage High	±1	±1	±10	±10	±10	±20		mA	V <sub>IN</sub> = 4.6 V
4		I <sub>INL</sub>	Input Current, Input Voltage Low	-0.7	-0.7	-0.7	-1	-1	-1	V <sub>IN</sub> = 0		
5	TIM	t <sub>on</sub>	Turn-ON Time		0.5			0.5		μs	See Switching Time Test Circuit	
6		t <sub>off</sub>	Turn-OFF Time		1.2			1.5				
7	SUPPLY	I <sub>-</sub>	Negative Supply Current	-2.5	-2.5	-2.5	-2.5	-2.5	-2.5	mA	I <sub>O</sub> = 0	V <sub>IN1</sub> = 0, All Other V <sub>IN</sub> = 4.6 V
8		I <sub>L</sub>	Logic Supply Current	2.5	2.5	2.5	2.5	2.5	2.5			
9	PLY	I <sub>-</sub>	Negative Supply Current	-2	-2	-200	-2	-2	-100	μA	V <sub>O</sub> = 10 V	All V <sub>IN</sub> = 4.6 V
10		I <sub>L</sub>	Logic Supply Current	1	1	100	2	2	100			

IBAF-B

## SWITCHING TIME TEST CIRCUIT



# 4-Channel MOS FET Switch Driver with Decode

*designed for . . .*

## ■ Interfacing Low Level Signals to FET Switches such as G115 and G123 Series Multi-Channel FET Switches

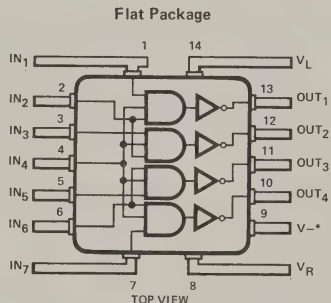
### BENEFITS

- Reduces System Component Requirements
  - Four Interface Circuits in One Chip
- Easily Interfaced
  - Inputs Compatible with Low Power TTL and DTL  $I_F = 200 \mu A$  Max
  - Output Current Sinking Capability 10 mA

### DESCRIPTION

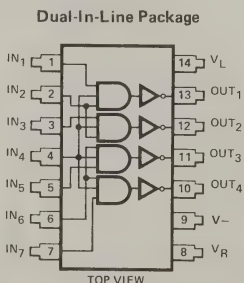
The D129 is a four-channel driver designed to provide the DC level-shifting and amplification functions needed to interface low-level logic outputs (0.7 to 2.2 V) and field-effect transistor switch inputs (up to 50 V peak-to-peak). With an input logic supply of 5 V, the output transistor emitter,  $V_-$ , may be set at any voltage between  $-5$  and  $-30$  V. In the ON state, the output collector will sink up to 10 mA of current, and in the OFF state will hold off voltages up to 50 V above  $V_-$ . Each of the four drivers has a 3-input logic gate, with each of the inputs either open or at positive logic "1", the driver will be ON. With any of the inputs either grounded or at positive logic "0", the driver will be OFF. Some of the logic inputs to the four gates are internally connected to facilitate decoding from a binary counter; however, one input to each gate provides a means for independent operation of each driver, if desired.

### PIN CONFIGURATIONS



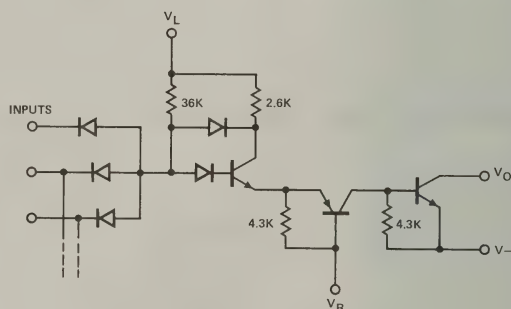
ORDER NUMBER: D129AL  
SEE PACKAGE 5

\* Common to Substrate and Base of Package



ORDER NUMBERS: D129AP OR D129BP  
SEE PACKAGE 11

### SCHEMATIC DIAGRAM



**ABSOLUTE MAXIMUM RATINGS**

$V_O$ to $V_-$ (A Suffix)	50 V
$V_O$ to $V_-$ (B Suffix)	36 V
$V_R$ to $V_-$ (A Suffix)	33 V
$V_R$ to $V_-$ (A Suffix)	24 V
$V_L$ to $V_R$	8 V
$V_{IN}$ to $V_R$	$\pm 6$ V
$V_{IN}$ to $V_{IN}$ (Any Other $V_{IN}$ Terminals)	6 V
Current (Any Terminal)	30 mA
Storage Temperature	-65 to 150°C

Operating Temperature (A Suffix) . . . . . -55 to 125°C  
 (B Suffix) . . . . . -20 to 85°C

**Power Dissipation\***

Flat Package\*\* . . . . . 750 mW  
 14 Pin DIP\*\*\* . . . . . 825 mW

\*All leads soldered or welded to PC board.

\*\*Derate 10 mW/°C above 75°C

\*\*\*Derate 11 mW/°C above 75°C

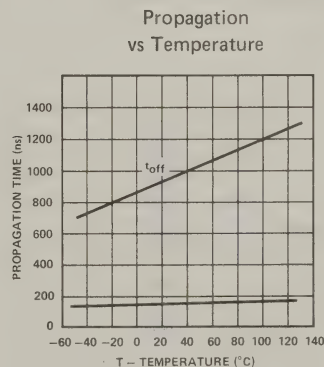
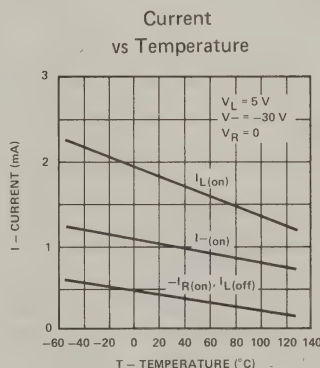
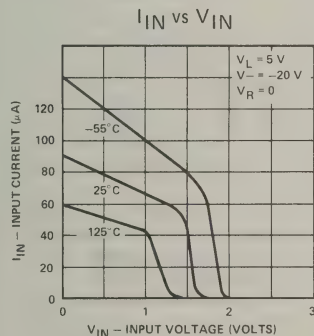
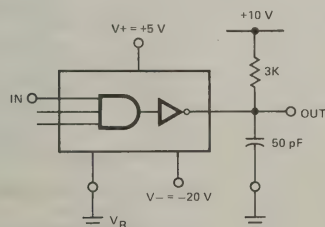
**ELECTRICAL CHARACTERISTICS**

All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

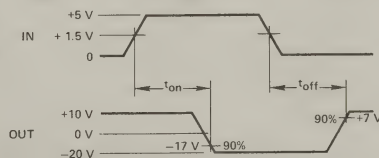
CHARACTERISTIC			MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V <sub>-</sub> = -20 V, V <sub>R</sub> = 0, V <sub>L</sub> = 5 V	
			D129A			D129B					
			-55°C	25°C	125°C	-20°C	25°C	85°C			
1 O U T	V <sub>OL</sub>	Output Voltage, Low	-19.3	-19.3	-19	-19.25	-19.25	-19	V	I <sub>O</sub> = 10 mA	V <sub>IN</sub> = 2.2 V, V <sub>L</sub> = 4.5 V
	V <sub>OL</sub>	Output Voltage, Low	-19.8	-19.8	-19.75			I <sub>O</sub> = 1 mA			
	3	I <sub>OH</sub>	Output Current, High	0.1	0.1	20	0.2	0.2	10	μA	V <sub>O</sub> = 10 V, V <sub>IN</sub> = 0.7 V
4  5 I N	I <sub>INH</sub> *	Input Current, Input Voltage High	0.25	0.25	5	1	1.0	5	μA	V <sub>IN</sub> = 5 V Input Under Test, V <sub>IN</sub> = 0 All Other Inputs	
	I <sub>INL</sub> *	Input Current, Input Voltage Low	-250	-200	-160	-250	-225	-200		V <sub>IN</sub> = 0, V <sub>L</sub> = 5.5 V	
6 T I M E	t <sub>on</sub>	Turn-ON Time		0.3			0.3		μs	See Switching Time Test Circuit	
	t <sub>off</sub>	Turn-OFF Time		1.5			1.5				
8 S U P P L Y	I <sub>-</sub>	Negative Supply Current		-2			-2.25		mA	V <sub>-</sub> = -20 V, V <sub>L</sub> = 5.5 V	One Channel "ON"
	I <sub>L</sub>	Logic Supply Current		3			3.3				All V <sub>IN</sub> = 0, All Channels "OFF"
	I <sub>-</sub>	Negative Supply Current		-10			-25		μA		
	I <sub>L</sub>	Logic Supply Current		0.75			1		mA		

\*Per gate input

IBAD-A

**TYPICAL CHARACTERISTICS****SWITCHING TIME AND TEST CIRCUIT**

$t_f < 100$  ns  
 $t_r < 100$  ns  
 $t_{pw} = 1$   $\mu$ s  
 $f = 100$  KHz



# Monolithic 2-Channel FET Switch Driver

*designed for . . .*



- Interfacing Low Level Signals to FET Switches
- Interfacing TTL to CMOS
- Interface from TTL to Other Logic Levels, i.e. PROM Program Levels

## BENEFITS

- Easily Interfaced
  - TTL, DTL and RTL Compatible
- Minimizes Switching Time
  - 150 ns Typical Propagation Time
- Versatile
  - Complementary Outputs
  - Up to 30 V Output Swing

## DESCRIPTION

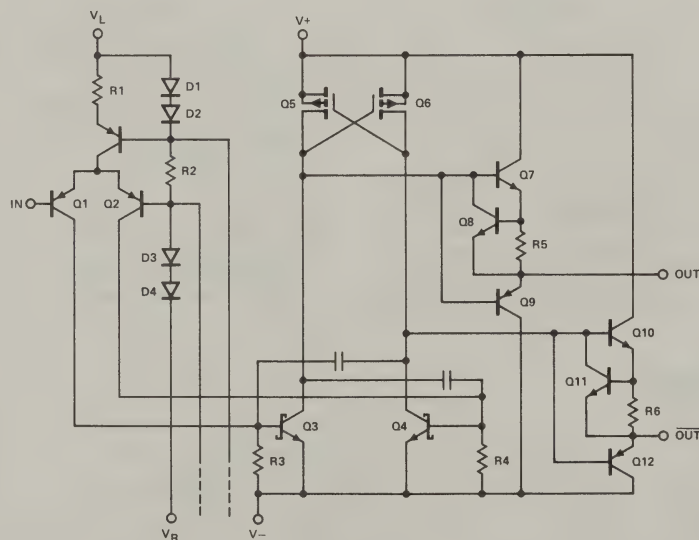
The D139 is a dual low level to high level voltage translator with complementary outputs. Uses include bipolar to MOS logic interface and bipolar logic to FET analog switch control.

The following characteristics of the input circuit provide an ideal interface to the common logic forms TTL, CMOS, and DTL: light loading ( $\approx 1/3$  TTL load) to "0" inputs, a 1.2 V trip point, and high input impedance with high breakdown to "1" inputs.

The output can drive up to 30 V peak-to-peak into pure capacitive loads or moderate resistive loads. Current source coupling between the input and output and split power supplies allow wide flexibility in the actual output voltage levels. Complementary outputs permit maximum application versatility, allowing functions such as double-throw analog switch control.

A positive logic "1" at the input provides a "1" at OUT and a "0" at  $\overline{\text{OUT}}$ .

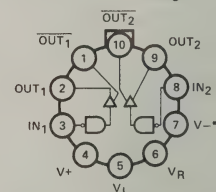
## SCHEMATIC DIAGRAM (Typical Channel)



Logic	OUT	$\overline{\text{OUT}}$
0	V-	V+
1	V+	V-

## PIN CONFIGURATIONS

### Metal Can Package

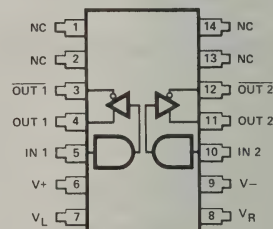


TOP VIEW

\*COMMON TO SUBSTRATE AND CASE

ORDER NUMBERS  
D139AA or D139BA  
SEE PACKAGE 2

### Dual-In-Line Package



TOP VIEW

ORDER NUMBERS D139AP  
OR D139BP  
SEE PACKAGE 11  
ORDER NUMBER D139CJ  
SEE PACKAGE 7



**ABSOLUTE MAXIMUM RATINGS**

V <sub>+</sub> to V <sub>-</sub>	36 V
V <sub>+</sub> to V <sub>R</sub>	36 V
V <sub>+</sub> to V <sub>O</sub>	36 V
V <sub>L</sub> to V <sub>R</sub>	8 V
V <sub>IN</sub> to V <sub>R</sub>	8 V
V <sub>R</sub> to V <sub>-</sub>	36 V
V <sub>L</sub> to V <sub>-</sub>	36 V
V <sub>O</sub> to V <sub>-</sub>	36 V
V <sub>L</sub> to V <sub>IN</sub>	8 V
Current (Any Terminal) DC	12 mA
Peak (Any Terminal)	100 mA
(200 μs pulse width, 100 pps)	

**Operating Temperature**

(A Suffix)	-55 to 125°C
(B Suffix)	-20 to 85°C
(C Suffix)	0 to 70°C

**Storage Temperature**

(A & B Suffix)	-65 to 150°C
(C Suffix)	-65 to 125°C

**Power Dissipation (L Package)\***

750 mW

**(P Package)\***

825 mW

**(J Package)\***

470 mW

**Thermal Resistance (θ<sub>JA</sub>, J Package)**

0.16°C/mW

\*All leads soldered or welded to PC board.

Derate L package 10 mW/°C above 75°C

Derate P package 11 mW/°C above 75°C

Derate J package 6.5 mW/°C above 25°C

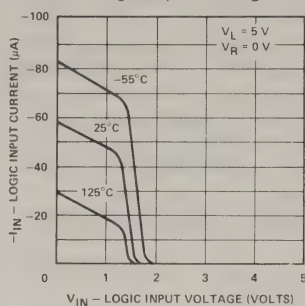
**ELECTRICAL CHARACTERISTICS**

All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

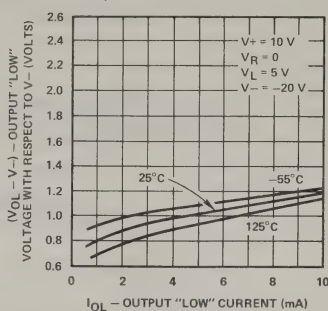
CHARACTERISTIC			D139AA/AP			D139BA/BP (D139CJ)			UNIT	TEST CONDITIONS, UNLESS NOTED: V <sub>+</sub> = 10 V, V <sub>L</sub> = 5 V, V <sub>-</sub> = -20 V, V <sub>R</sub> = 0	
			(MIN)/MAX LIMITS			(MIN)/MAX LIMITS					
			-55°C	25°C	125°C	-20°C (0°C)	25°C	85°C (70°C)			
1	V <sub>OH</sub> /V <sub>OH</sub>	Output Voltage, High (V <sub>+</sub> to V <sub>O</sub> )	1.1	0.9	0.7	1.1	0.9	0.7	V	I <sub>OUT</sub> = -10 μA	V <sub>IH</sub> = 2 V for V <sub>OH</sub> /V <sub>OL</sub> , V <sub>IL</sub> = 0.8V for V <sub>OH</sub> /V <sub>OL</sub>
2			1.5	1.5	1.5	1.5	1.5	1.5		I <sub>OUT</sub> = -2 mA	
3	V <sub>OL</sub> /V <sub>OL</sub>	Output Voltage, Low (V <sub>O</sub> to V <sub>-</sub> )	1.3	1.1	0.9	1.3	1.1	0.9		I <sub>OUT</sub> = 10 μA	
4			1.5	1.5	1.5	1.5	1.5	1.5		I <sub>OUT</sub> = 2 mA	
5	I <sub>INH</sub>	Input Current, Input Voltage High		10	20		10	20	μA	V <sub>IN</sub> = 5 V	
6	I <sub>INL</sub>	Input Current, Input Voltage Low	(-600)	(-500)	(-500)	(-600)	(-500)	(-500)		V <sub>IN</sub> = 0	
7	t <sub>(+)</sub>	Switching Time, Low to High, Delay Plus Rise Time		170			170		ns	See Switching Time Test Circuit (C <sub>L</sub> = 35 pF)	
8	t <sub>(-)</sub>	Switching Time, High to Low, Delay Plus Fall Time		200			200				
9	I <sub>+</sub>	Positive Supply Current		0.1			0.1		mA	Input Voltage High or Input Voltage Low	
10	I <sub>L</sub>	Logic Supply Current		4.0			4.0			V <sub>IN1</sub> = V <sub>IN2</sub> = 5 V	
11	I <sub>-</sub>	Negative Supply Current		-3.0			-3.0			V <sub>IN1</sub> = V <sub>IN2</sub> = 0 V	
12	I <sub>RH</sub>	Reference Supply Current Input Voltage High		(-1.6)			(-1.6)				
13	I <sub>RL</sub>	Reference Supply Current, Input Voltage Low		(-1.1)			(-1.1)				

CMOA

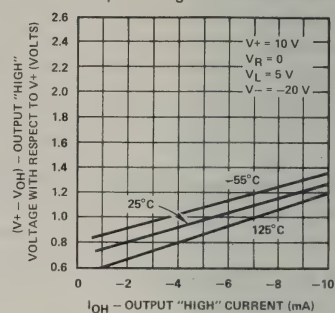
## TYPICAL CHARACTERISTICS

Logic Input Current vs  
Logic Input Voltage

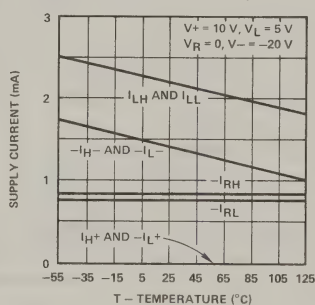
Output "Low" Characteristic



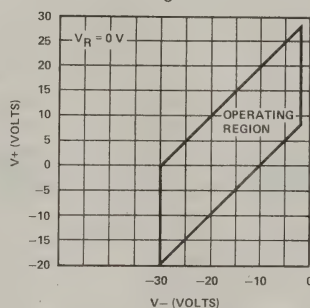
Output "High" Characteristic



Supply Current vs Temperature



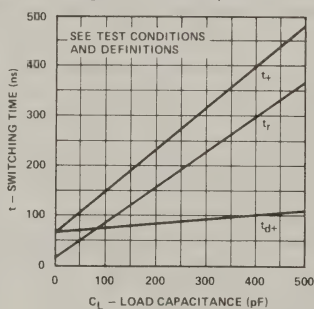
Selecting V+ and V-



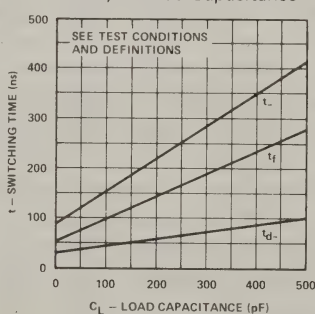
Selecting V+ and V-

The output swings between  $V_+$  and  $V_-$  ( $V_{OH} \cong V_+$  and  $V_{OL} \cong V_-$ ). Select  $V_+$  and  $V_-$ , within the operating region of curve at left, to provide the desired output swing. Note that  $V_-$  can be  $-2.0$  V to  $-30$  V and  $V_+ - V_-$  must be at least 10 V.

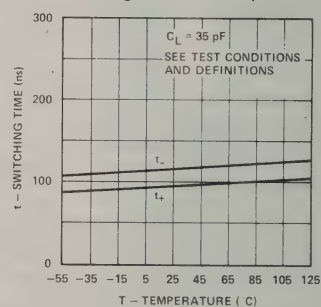
Switching Time, Low to High, vs Load Capacitance



Switching Time, High to Low, vs Load Capacitance

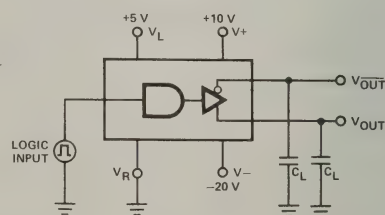
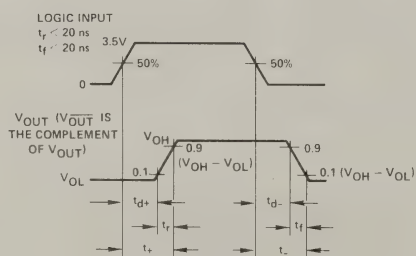


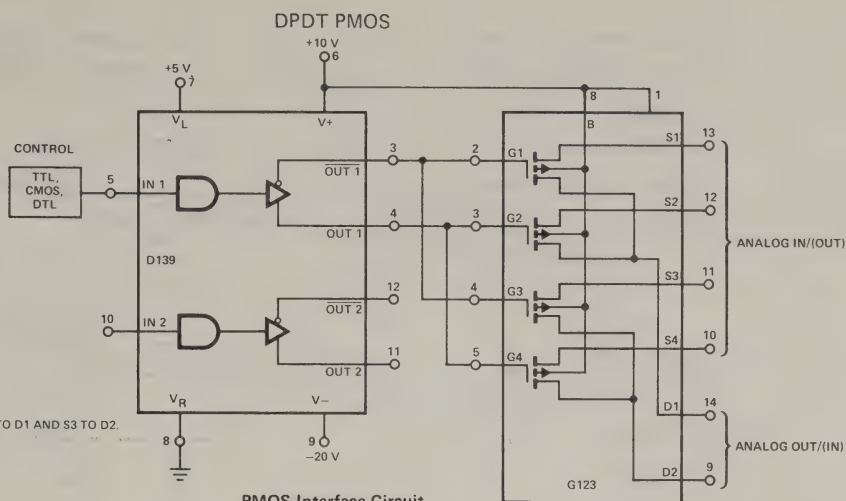
Switching Time vs Temperature



## TEST CONDITIONS AND DEFINITIONS

Switching Time Test Circuit

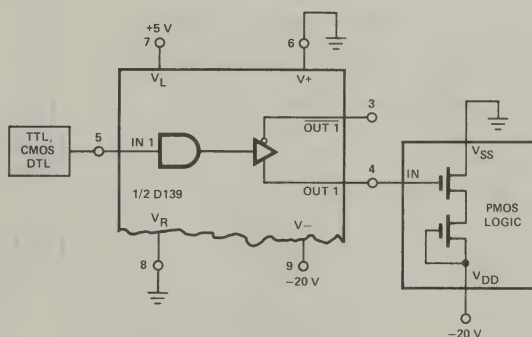


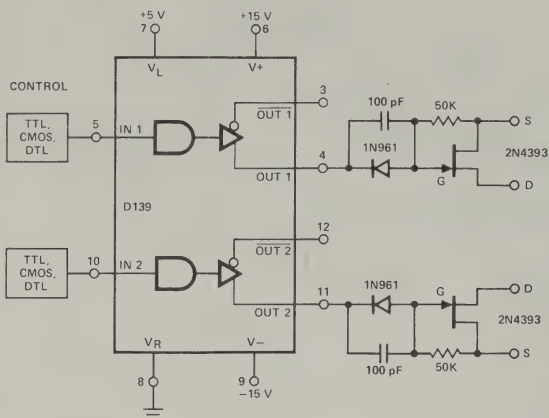


A "1" FROM CONTROL CONNECTS S2 TO D1 AND S3 TO D2.  
 $V_{AN}$  RANGE = +10 V TO -10 V

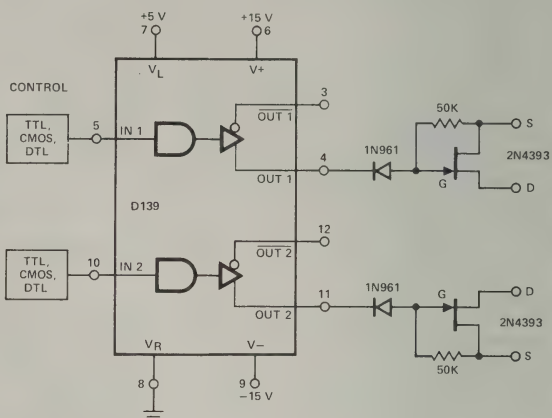
**Driving PMOS Analog Switches.** The D139 output swing is dictated by the analog signal range.  $V_{OH}$  is the PMOS "OFF" level and must equal the most positive analog voltage.  $V_{OL}$  is the PMOS "ON" level and must be 10 V more negative than the most negative analog voltage. Therefore for  $V_{AN} = \pm 10$  V  $\rightarrow V_+ = +10$  V and  $V_- = -20$  V. PMOS control is make-before-break.

## PMOS LOGIC INTERFACE



Fast Dual SPST, NJFET, for  
Low Frequency Signals (1)

THE 2N4393 WILL BE "ON" FOR A "1" FROM CONTROL.  
 $V_{AN}$  RANGE = +10 V TO -10 V.

Dual SPST, NJFET for High  
Frequency Signals (1)

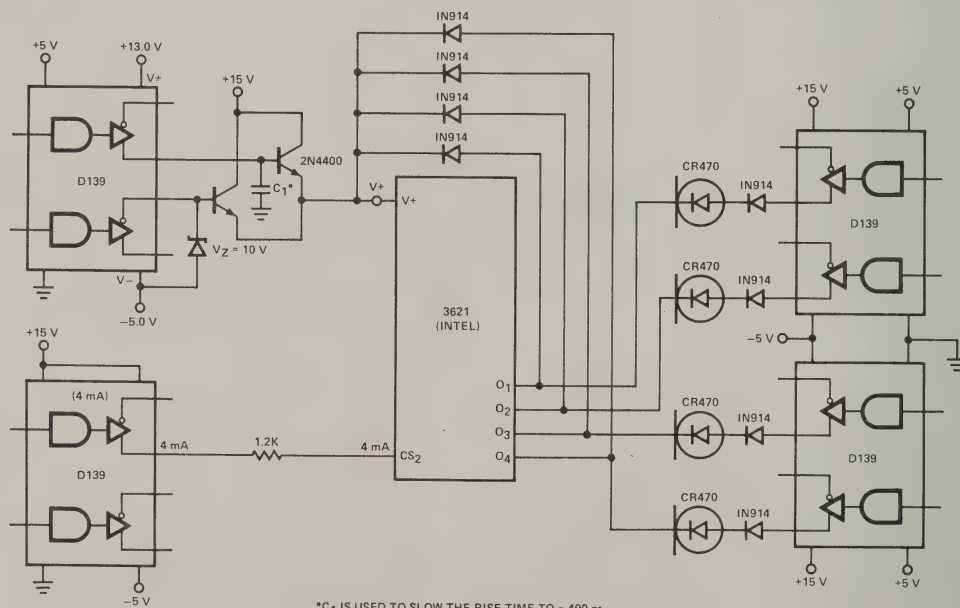
THE 2N4393 WILL BE "ON" FOR A "1" FROM CONTROL.  
 $V_{AN}$  RANGE = +10 V TO -10 V.

Figure 3

**Driving NJFET Analog Switches.**  $V_{OH}$  is the "ON" NJFET level and must be isolated from the gate by a series diode as shown above to prevent forward gate current.  $V_{OL}$  is the "OFF" NJFET level and must be more negative than the most negative analog signal voltage by  $(|V_{GS(off)}| + 2 \text{ V})$ . NJFET control is break-before-make.

(1) See Siliconix Application Note "Driver Circuits for the J-FET Analog Switch" AN73-5, August 1973.

## APPLICATIONS

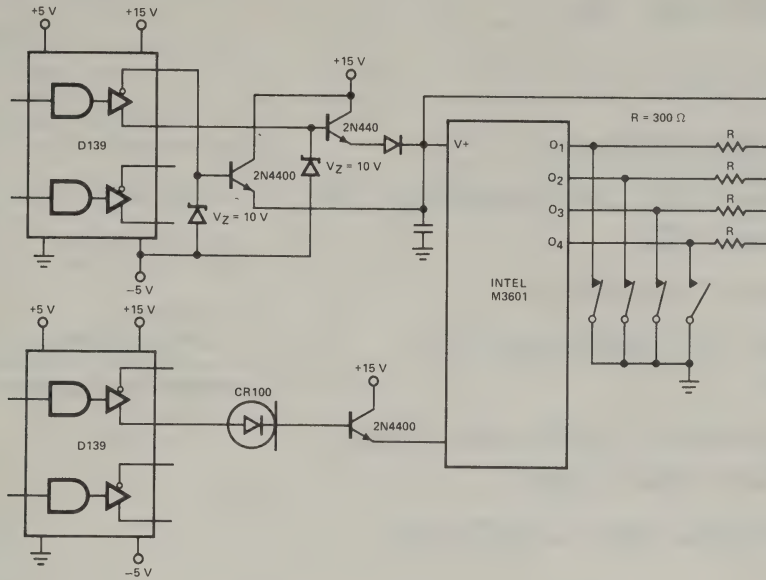


\* $C_1$  IS USED TO SLOW THE RISE TIME TO ~400 ns

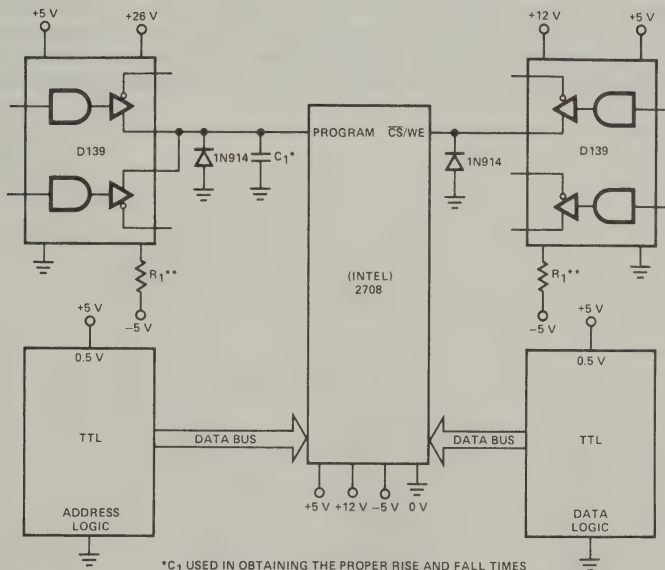
D139 Used in Programming the Intel 3621 PROM

Figure 4





D139 Used in Programming the Intel 3601 PROM  
Figure 5



D139 Used in Programming the Intel 2708 PROM  
Figure 6

**D139 2-Channel Interface.** The D139 may be used to interface 0.5 V TTL to CMOS Logic by setting  $V_L$ ,  $V_R$ ,  $V_+$  and  $V_-$  to the proper levels. If 0 to 5 V TTL levels are to be used to control the switch,  $V_L$  should be set to 5 V and  $V_R$  grounded.

$V_+$  and  $V_-$  may be set to whatever levels are needed. The operating region of the D139 is determined by the graph of  $V_+$  vs  $V_-$ .

Note,  $V_-$  must be at least 2 V below  $V_R$  in order for the D139 to operate. See the  $V_+$  vs  $V_-$  graph for selecting the supply voltages within the operating region.

# Dual Driver IC

## designed for . . .

- Analog Multiplexing
- Interfacing from Low-Level Logic to MOS Power FETs
- Logic Level Translation
- Driver for PIN Diodes and FET Switches
- Timing Circuits (Oscillators, Pulse Generators, and Timers)
- Differential-Output Line Driver

### BENEFITS

- Complementary Outputs
- Wide Output Swing:
  - 33 V at  $\pm 40$  mA
- Fast Switching:
  - 70 ns Delay Time
- Variable Input Threshold
- Low Power Drain

### DESCRIPTION

The D169 is a versatile high-voltage dual driver with complementary outputs. Low-level logic inputs can be translated up to  $\pm 33$  V output levels. A differential input stage with adjustable threshold provides high input impedance and easy interfacing to low-level logic or analog inputs. Current-source coupling to the output stage allows wide flexibility in output voltage levels. The complementary emitter-follower outputs can source and sink currents of up to  $\pm 40$  mA with an output swing of up to 33 V. This output stage is excellent for driving capacitive loads; such as power MOSFETs, long cables, or timing capacitors. The output stage can be operated from single or split supplies. Each channel of the dual D169 has two separate outputs that are complementary (OUT and  $\overline{\text{OUT}}$ ). This two-phase output capability can be very useful for driving power MOSFET configurations.

### TYPICAL APPLICATIONS

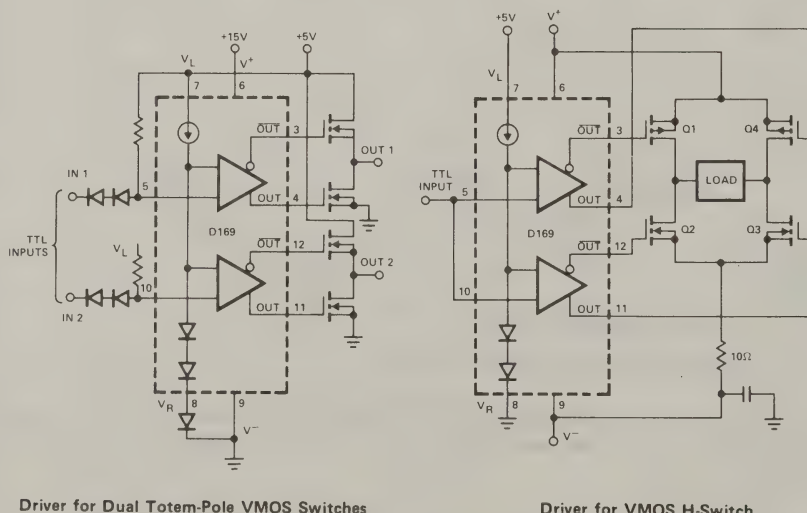
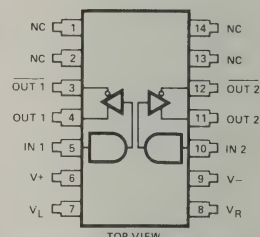


Figure 1

### PIN CONFIGURATIONS

#### Dual-In-Line Package



ORDER NUMBERS D169AP  
SEE PACKAGE 11  
D169AK OR D169CK  
SEE PACKAGE 9  
D169CJ  
SEE PACKAGE 7

LOGIC	OUT	$\overline{\text{OUT}}$
0	V <sub>-</sub>	V <sub>+</sub>
1	V <sub>+</sub>	V <sub>-</sub>

## ABSOLUTE MAXIMUM RATINGS

$V^+$ to $V^-$ , $V^+$ to $V_R$ , and $V^+$ to $V_O$ .....	36 V
$V_L$ to $V_R$ , $V_{IN}$ to $V_R$ , and $V_L$ to $V_{IN}$ .....	10 V
$V_R$ to $V^-$ , $V_L$ to $V^-$ , and $V_O$ to $V^-$ .....	36 V
Current (Any Terminal) DC .....	40 mA
Peak (Pulsed 1 ms, 10% Duty Cycle) .....	150 mA
Operating Temperature—"A" Suffix	
(A Suffix) .....	-55 to 125°C
(C Suffix) .....	0 to 70°C
Storage Temperature	
(A Suffix) .....	-65 to 150°C
(C Suffix) .....	-65 to 125°C

## Power Dissipation

"P" Package* .....	825 mW
"J" Package* .....	470 mW
Thermal Resistance ( $\theta_{JA}$ , J Package) .....	0.16°C/mW

\*All leads soldered or welded to PC board. Derate P package 11 mW/°C above 75°C. Derate J package 6.5 mW/°C above 25°C.

## ELECTRICAL CHARACTERISTICS

All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC			25°C TYP†	D169AP			D169CJ			UNIT	TEST CONDITIONS, UNLESS NOTED: V+ = 15 V, VL = 5 V, V- = -15 V, VR = 0	
				MAX LIMITS			MAX LIMITS					
				-55°C	25°C	125°C	0°C	25°C	70°C			
1	VOH/VOH	Output Voltage, High (V+ to VO)	0.7	1.1	1.0	1.0	1.1	1.0	1.0	V	IOUT = 1 mA	VIH = 2 V for VOH/VOL VIL = 0.8 V for VOH/VOL
2			1.5	2.5	2.5	3.1	2.5	2.5	3.1		IOUT = 40mA	
3	VOL/VOL	Output Voltage, Low (VO to V-)	-.75	-1.2	-1.2	-1.2	-1.2	-1.2	-1.2		IOUT = 1 mA	
4			-2.2	-3.0	-3.0	-4.0	-3.0	-3.0	-4.0		IOUT = 40 mA	
5	IINH	Input Current, Input Voltage High	1.0		5.0	5000		5.0	200	nA	VIN = 3 V	
6	INL	Input Current, Input Voltage Low	-25	-100	-50	-50	-70	-50	-50	µA	VIN = 0	
7	t(+)	Switching Time, Low to High, Delay Plus Rise Time	100		170			170		ns	See Switching Time Test Circuit (CL = 35 pF)	
8	t(-)	Switching Time, High to Low, Delay Plus Fall Time	130		200			200				
9	VXO	Switching Crossover Level	.9							V	200 pF Load	
10	I+	Positive Supply Current	—		0.1			0.1		mA	No Load, VIN1 = VIN2 = 0V	
11	IL	Logic Supply Current	3.2		4.0			4.0				
12	I-	Negative Supply Current	-2.2		-3.0			-3.0				
13	IR	Reference Supply Current	1.0		1.5			1.5				

†Typical values are for Design Aid only, not guaranteed and not subject to production testing.

CMOB

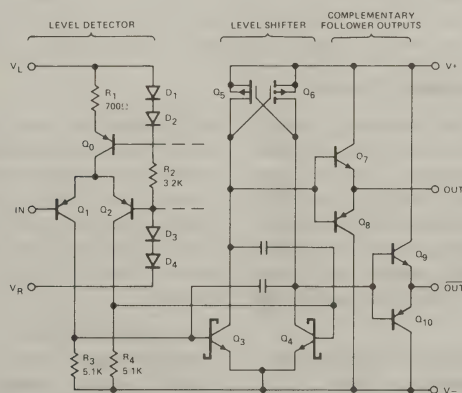


Figure 2. Schematic Diagram, One Channel

## ELECTRICAL CHARACTERISTICS (CONT'd)

## SWITCHING TESTS

## TEST CONDITIONS

TEST	$V_L$	$V_R$	$V^+$	$V^-$	$C_L$	$R_L$	$V_{IN}$		WAVE-FORMS
							$V_{IL}$	$V_{IH}$	
1	5.0V	0.7V	10V	0	200 pF	—	1.0V	3.5V	A
2	5.0V	0.7V	15V	0	0	510 $\Omega$	1.0V	3.5V	B
3	5.0V	0.7V	10V	0	200 pF	—	1.0V	3.5V	B
4	5.0V	0.7V	10V	0	1000 pF	—	1.0V	3.5V	B
5	5.0V	0	15V	-15V	200 pF	—	0	3.5V	B
6	5.0V	0	15V	-15V	1000 pF	—	0	3.5V	B

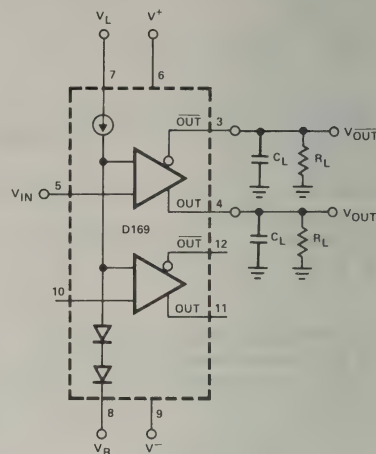
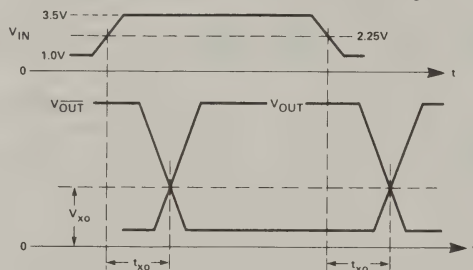
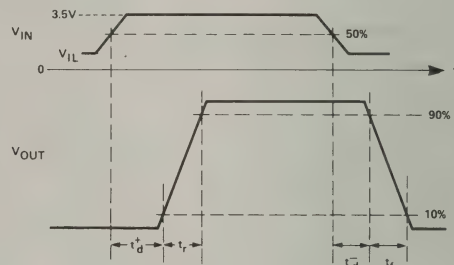


Figure 17. Switching Test Circuit



WAVEFORMS A



WAVEFORMS B

Table 1.

Test Conditions	Test 2 (Fig. 17)	Tests 5 & 6 (Fig. 17)		Tests 3 & 4 (Fig. 17)		Units
	Resistive, $I_O = 25\text{ mA}$	$V^+ = +15V, V^- = -15V$		$V^+ = +15V, V^- = 0$		
		Capacitive Load		Capacitive Load		
		200 pF	1000 pF	200 pF	1000 pF	
	Typ	Typ	Typ	Typ	Typ	
Low-to-High Delay Time, $t_d^+$	70	95	220	110	230	ns
Rise Time, $t_r^+$	35	60	240	55	200	ns
High-to-Low Delay Time, $t_d^-$	50	50	80	55	80	ns
Fall Time, $t_f^-$	25	110	400	80	275	ns

## Complementary Emitter-Follower Output

Transistors  $Q_7$  through  $Q_{10}$  form complementary emitter-follower outputs connected to each side of the  $Q_3, Q_4$  level shifter. This permits resistive loads requiring up to 40 mA to be driven at high speeds (rise and fall times under 50 ns—see Figure 10). Also high peak currents are available to drive capacitive loads (see Figures 11 and 12 for capacitive switching data). The switching times are generally independent of output swing, except for the fall time which is influenced by the negative rail,  $V^-$ .

The PNP transistors have a relatively high collector series resistance. Consequently, when a steady-state current is being drawn by the PNP which exceeds about 2 mA, the transistor becomes saturated and minority carrier storage takes place in the base and collector regions. Upon a change of state, a

storage delay occurs which can be substantial if a large current is being switched (see Figures 6 and 16). This delay can be utilized when a long "dead time" is needed during change of state and when only the portion of the voltage waveform more positive than zero is of interest. This storage delay does not occur when capacitive loads are being driven, regardless of output levels, or when the load and  $V^-$  are returned to ground.

The output levels as a function of DC output current are shown in Figures 13 and 14. Note that no current limiting is used in the output stages. Consequently, care must be exercised to avoid exceeding the maximum current rating of the device.



# TYPICAL CHARACTERISTICS

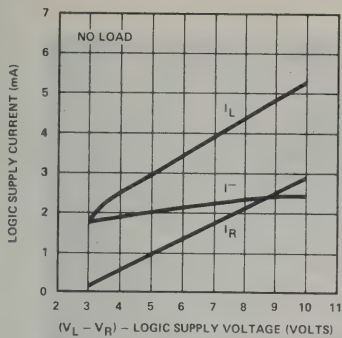


Figure 3. Supply Current Variation with Logic Supply

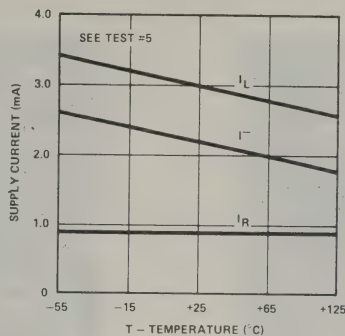


Figure 4. Effect of Temperature on Supply Currents

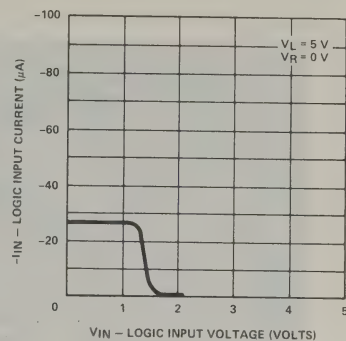


Figure 5. Logic Input Current vs. Logic Input Voltage

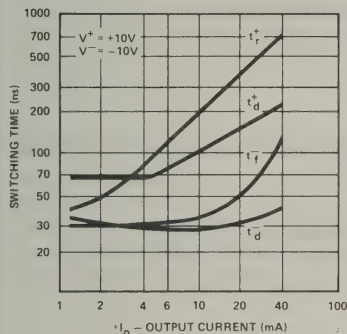


Figure 6. Switching Times with Resistive Load

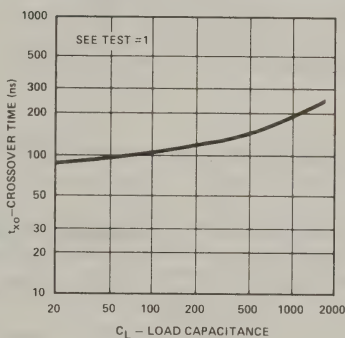


Figure 7. Effect of Load Capacitance on Crossover Time

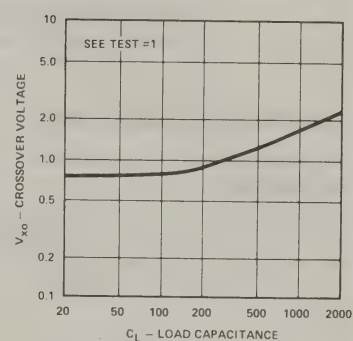


Figure 8. Effect of Load Capacitance on Crossover Level

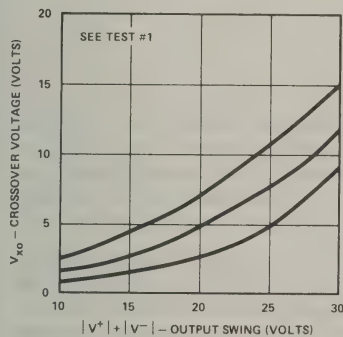


Figure 9. Effect of Voltage Output on Crossover Level

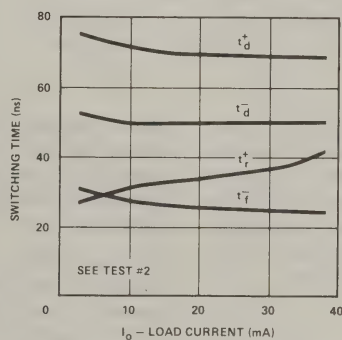


Figure 10. Resistive Load Switching

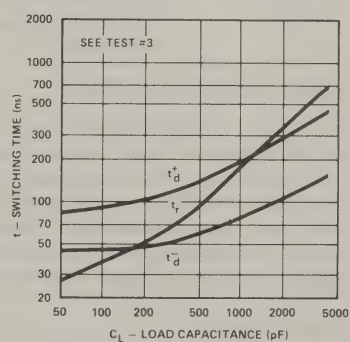


Figure 11. Switching Times with Capacitive Load

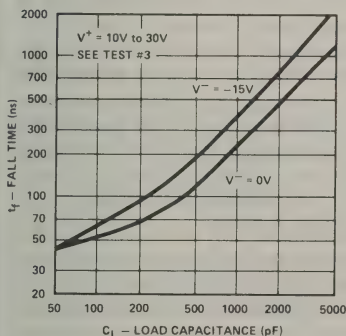


Figure 12. Fall Time with Capacitive Load

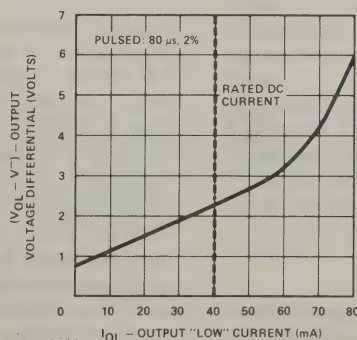


Figure 13. Output "Low" Characteristic

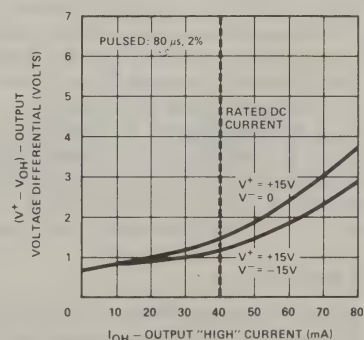


Figure 14. Output "High" Characteristic

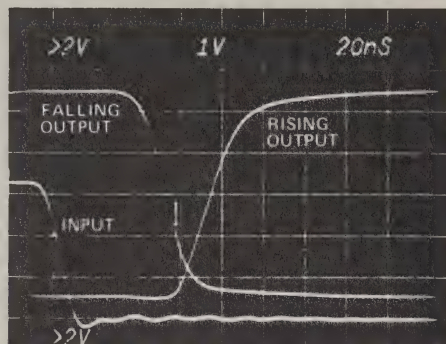


Figure 15. Switching Waveform

40 mA Load,  $V^+ = 20V$ ,  
 $V^- = 0$

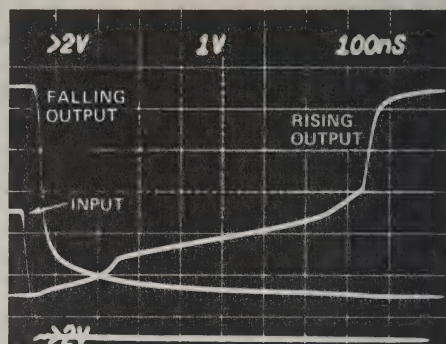


Figure 16. Switching Waveform

$\pm 40$  mA Load,  $V^+ = 10V$ ,  
 $V^- = -10V$

## OPERATING GUIDELINES

For proper performance of the D169 circuit, certain guidelines must be followed for the power supply and input terminals. These are listed below:

TERMINAL	ALLOWABLE CONDITIONS
$V^+$ (Pin 6) $V^-$ (Pin 9)	Any positive voltage Any negative voltage or } $10V \leq V^+ - V^- \leq 36V$ zero volts
$V_R$ (Pin 8)	$\geq V_{EE} + 1V$ (Input Threshold = $V_R + 1.4V$ )
$V_L$ (Pin 7)	$V_L - V_R \geq 4V$
IN1L, IN2L (Pins 5, 10)	$\geq V_{EE} + 1V$
IN1H, IN2H (Pins 5, 10)	$\geq V_{EE} + 3V$

## CIRCUIT OPERATION

The D169 circuit has three sections: (1) an input level detector, (2) a level shifter, and (3) a pair of complementary emitter-follower outputs. This arrangement provides a high input impedance, high output drive capability, and compatibility with a wide range of power supply levels. The input threshold level can be easily varied to accept various logic levels. Output swing is set by the  $V^+$  and  $V^-$  power supply levels.

### Level Detector

Transistors  $Q_1$  and  $Q_2$  form a differential input pair. Transistor  $Q_0$ , resistor  $R_1$ , and diodes  $D_1$ ,  $D_2$  form a current source of about 1 mA which drives the common emitter connection. The voltage between supply levels  $V_L$  and  $V_R$  determines the value of the current source and the current through the bias string (diodes  $D_1$  through  $D_4$  and resistor  $R_2$ ). The current from the supply  $V_L$  and the current out of the terminals  $V_R$  and  $V^-$  is shown in Figure 3. Temperature variations are shown in Figure 4. The voltage on the base of  $Q_2$  determines the trip point where the circuit changes state. With  $V_R$  grounded, the trip point is about 1.4 volts, depending somewhat on the voltage  $V_L$ . The input characteristics are shown in Figure 5.

### Level Shifter

Schottky-clamped transistors  $Q_3$  and  $Q_4$  along with P-channel MOSFETs  $Q_5$  and  $Q_6$  form a complementary-coupled switching stage. This configuration draws no idle current and per-

mits a change of state within 100 ns after the input signal passes the trip point. The circuit delays are such that the switching action approaches a "break-before-make" sequence as shown in Figure 15. The response times are essentially independent of the input signal level and rise time.

The time measured from the input signal step to where the output waveforms from OUT and  $\overline{OUT}$  cross is called *crossover time*. The voltage level at that time with respect to  $V^-$  is called *crossover voltage*. This point is of importance when driving certain loads where a break-before-make action is necessary to avoid high current surges. The crossover time is essentially independent of output voltage swing, but is affected by the load capacitance as shown in Figure 7. The delay time of the negative going waveform from OUT and  $\overline{OUT}$  is not significantly affected by load capacitance; however, the delay time of the positive going waveform experiences a delay which is fairly sensitive to load capacitance. This feature reduces the dependence of crossover voltage on the load capacitance as shown in Figure 8. However, the output voltage swing does exert considerable influence upon crossover level as indicated in Figure 9.

In order to provide adequate drive to  $Q_3$  and  $Q_4$ , the voltage at the collector of the differential pair must be more positive than the  $V^-$  level plus the base emitter drop of the Schottky transistors. This dictates that the "low" level of  $V_{IN}$  should exceed  $V^-$  by at least one volt.

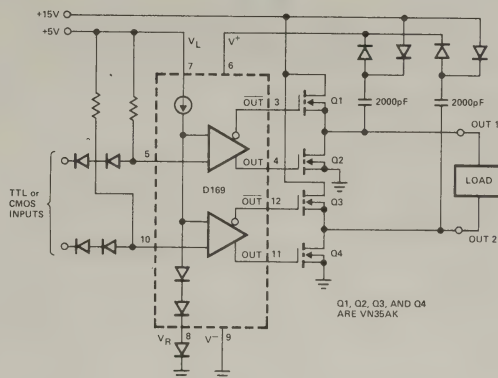


Figure 18. Totem-Pole Driver with Bootstrapping

### Totem-Pole Driver with Bootstrapping

When driving VMOS in a totem-pole output configuration (see Figure 18), it is necessary to have the gate voltage 10 to 15 volts positive with respect to the source in order to handle load currents near the VMOS maximum ratings. The D169 lends itself to bootstrapping because of its high voltage ratings.

In the circuit shown, the voltage on the 2000 pF bootstrap capacitors is applied via diode "OR" gates to the  $V^+$  terminal. Therefore, regardless of which output is high, 30 volts is present at  $V^+$ . Maximum switching frequency is determined by the input capacitance of the VMOS transistors used.

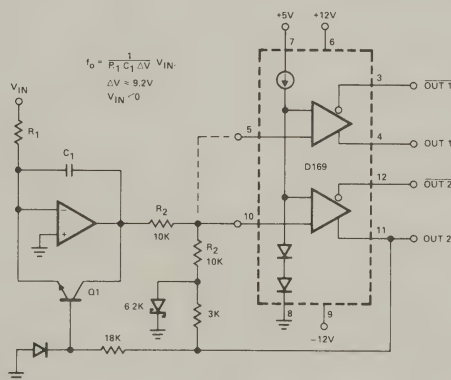


Figure 19. D169 Used as a Voltage-to-Frequency Converter

### Voltage-to-Frequency Converter

A simple, low-cost VFC can be designed using the D169 and a single op amp (see Figure 19). The D169 serves as a level detector and provides complementary outputs. The op amp is used to integrate the input signal  $V_{IN}$  with a time constant of  $R_1C_1$ . The input, which must be negative, causes a positive ramp at the output of the integrator which is then summed with a negative zener voltage. When the ramp is positive enough to cause the D169 input (pin 10) to exceed the logic threshold of 1.4 V, then the D169 outputs change state and OUT 2 flips from negative to positive. This positive output of

approximately 11 V puts transistor  $Q_1$  into saturation which then resets the integrator to near zero. The integrator peak differential voltage  $\Delta V$  will be approximately 9.2 V. The output frequency  $f_o$ , neglecting the short reset interval, will be

$$f_o = \frac{1}{R_1 C_1 \Delta V} V_{IN}, V_{IN} < 0$$

The pulse repetition rate,  $f_o$ , is directly proportional to the negative input voltage  $V_{IN}$ .







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# Index

## TELECOMMUNICATIONS

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## LOOP DISCONNECT DIALERS

Product	Description	Application
DF320/DF320A/DF322 DF328	Crystal Oscillator LC or Crystal Oscillator	Replacing Conventional Rotary Dial Phones with Push Button Keyboard Phones

*Stresses listed under "Absolute Maximum Ratings" may be applied (one at a time) devices without resulting in permanent damage. This is a stress rating only and not subject to production testing. Exposure to absolute maximum rating conditions for extended periods may effect device reliability.*

# CMOS Loop Disconnect Dialers



DF320 DF320A DF322

*designed for . . .*

- Push Button Telephones
- Repertory Dialers
- Telex
- Mobile Telephones
- Security and Fire Alert Systems
- Emergency Number Dialers

## BENEFITS

- Eliminates the Need for Regulated Supplies
  - 2.5 V to 5.5 V  $V_{DD}$  Range
- Minimizes Power Consumption
  - Standby Dissipation — 6  $\mu$ W
- Low Cost
  - Simple Support Circuitry
  - Power On Reset
- Minimizes External Components
  - On Chip Circuitry for: Keyboard De-bouncing; Last Number Repeat; Input Pull Up/Pull Down Terminations
- Versatile
  - Selectable Mark/Space Ratios, Impulsing Speeds
  - Hold Facility to Delay Impulsing
  - Fixed IDP: 8 Times Impulsing Period

## DESCRIPTION

The DF320 series of monolithic CMOS Loop Disconnect Dialers each contain all the logic necessary to interface a standard double contact keyboard to a telephone system requiring loop disconnect signalling.

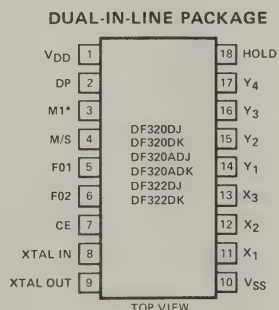
A dial pulsing output and two masking output options are provided to control the impulsing (loop disconnect) and muting functions. The circuit is capable of storing a number string of up to 20 digits and re-dialing this stored number automatically at a later time, initiated by a RE-DIAL input code. Impulsing mark/space ratio (M/S), and impulsing rate are pin programmable to meet most telephone authority specifications.

The use of Siliconix low voltage CMOS technology allows operation with an unregulated supply voltage down to a guaranteed minimum of 2.5 V. This feature, together with low operating current, negligible standby current and high noise immunity make the DF320 series easy to interface to long telephone lines.

External component count is minimized by the inclusion of an on-chip clock oscillator, high impedance pull-down terminations to programming inputs as well as pull-up terminations to the keyboard giving direct interfacing.

The DF320 provides the functions most commonly required in the push button telephone application. M1 is the masking option which remains at logic "1" throughout the dialing sequence. The DF322 is identical to the DF320 except that M2 is offered instead of M1. The M2 masking option is at logic "1" only during impulsing, allowing the telephone line to be monitored during the IDP. The DF320A has an extended post impulsing pause of 500 ms.

## PIN CONFIGURATION



\*M2 ON DF322DJ, DF322DK

ORDER NUMBERS DF320DJ, DF320ADJ OR DF322DJ  
SEE PACKAGE 19  
ORDER NUMBERS DF320DK, DF320ADK OR DF322DK  
SEE PACKAGE 23

2

Telecommunications

## ABSOLUTE MAXIMUM RATINGS

$V_{DD} - V_{SS}$  . . . . .  $-0.3\text{ V to }8\text{ V}$   
 Voltage on Any Pin . . . . .  $V_{SS} - 0.3\text{ V to }V_{DD} + 0.3\text{ V}$   
 Current at Any Pin . . . . .  $10\text{ mA}$   
 Operating Temperature . . . . .  $-40\text{ to }+85^{\circ}\text{C}$

Storage Temperature (K Package). . . . .  $-65\text{ to }+150^{\circ}\text{C}$   
 (J Package). . . . .  $-65\text{ to }+125^{\circ}\text{C}$   
 Power Dissipation (J and K Package). . . . .  $450\text{ mW}$

\*Derate  $6.3\text{ mW}/^{\circ}\text{C}$  above  $25^{\circ}\text{C}$ . All leads soldered to PC board.

## ELECTRICAL CHARACTERISTICS

All voltages referenced to  $V_{SS}$  unless otherwise noted.

Characteristic				Min	Typ*	Max	Units	Test Conditions Unless Noted: V <sub>DD</sub> = 3.0 V, T <sub>A</sub> = 25°C f <sub>CLK</sub> = 3.57945 MHz			
1	SUP	V <sub>DD</sub>	Supply Voltage Operating Range	2.5		5.5	V				
2		I <sub>DSS</sub>	Standby Supply Current		2.0	10.0	μA	CE = V <sub>SS</sub>			
3		I <sub>DD</sub>	Operating Supply Current		155	250	μA	3.579545 MHz Crystal, C <sub>XTALOUT</sub> = 12 pF			
4	INPUT	I <sub>IL</sub>	Pull-Up Transistor Source Current	-0.5	-6	-10.0	μA	V <sub>IN</sub> = V <sub>SS</sub>	X <sub>1</sub> , X <sub>2</sub> , X <sub>3</sub> , Y <sub>1</sub> , Y <sub>2</sub> , Y <sub>3</sub> , Y <sub>4</sub>		
5		I <sub>IH</sub>	Input Leakage Current		0.1		nA	V <sub>IN</sub> = V <sub>DD</sub>			
6		I <sub>IL</sub>	Input Leakage Current		-0.1		nA	V <sub>IN</sub> = V <sub>SS</sub>	M/S, F01, F02, Hold		
7		I <sub>IH</sub>	Pull-Down Transistor Sink Current	0.5	3.0	10.0	μA	V <sub>IN</sub> = V <sub>DD</sub>			
8	OUT	V <sub>IL</sub>	Logic "0" Level			0.65	V		All Inputs		
9		V <sub>IH</sub>	Logic "1" Level	2.45			V				
10		V <sub>OL</sub>	Voltage Levels	Low Level		0	0.01	V	No Load	DP, M1, M2	
11		V <sub>OH</sub>		High Level	2.99	3		V			
12		I <sub>OL</sub>	Drive Current	N-Channel Sink	0.5	1.5		mA			V <sub>OUT</sub> = 2.3 V
13		I <sub>OH</sub>		P-Channel Source	-0.5	1.5		mA			V <sub>OUT</sub> = 0.7 V
14	DYNAMIC	t <sub>r</sub>	Output Rise Time		1.0		μs	DP, M1, M2, C <sub>L</sub> = 50 pF			
15		t <sub>f</sub>	Output Fall Time		1.0		μs				
16		f <sub>CLK</sub>	Maximum Clock Frequency	3.58			MHz	3.579545 MHz Crystal			
17		M/S	Mark to Space Ratio		2:1			Note 1			
18					3:2						
19		IDP	Interdigital Pause		8T		ms	T = Selected Impulsing Period, Note 1			
20			Impulsing Rate = 1T		10		Hz	Note 1			
21					16						
22					20						
23					932						
24	t <sub>ON</sub>	Clock Start Up Time		1.5	4	ms	Timed from CE = Logic "1"				
25	C <sub>IN</sub>	Input Capacitance		5.0		pF	Any Input				
26	POIP	Post Impulsing Pause		0.3T		ms	DF320, DF322, DF320A	T = Selected Impulsing Period			
27					5T				ms		

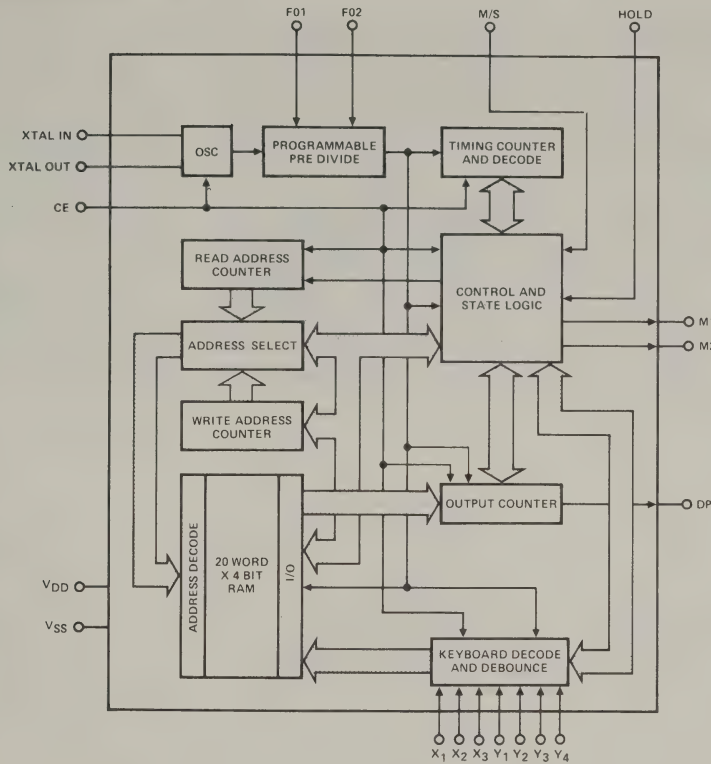
\*Typical parametric values are for Design Aid Only, not guaranteed and not subject to production testing. Timing waveforms are subject to production functional test.

## NOTES:

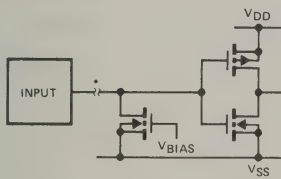
- See Pin Function, Table 1



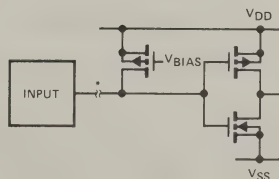
# FUNCTIONAL BLOCK DIAGRAM



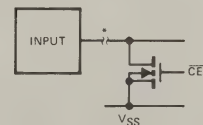
## INPUT OUTPUT SCHEMATICS



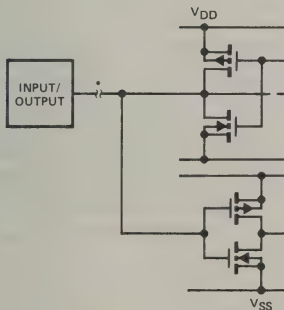
M/S, F01, F02, HOLD  
Figure 1



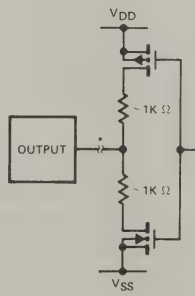
X<sub>1</sub>, X<sub>2</sub>, X<sub>3</sub>, Y<sub>1</sub>, Y<sub>2</sub>, Y<sub>3</sub>, Y<sub>4</sub>  
Figure 2



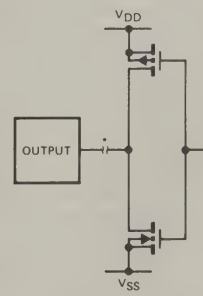
XTAL IN  
Figure 3



CE  
Figure 4



DP, M1, M2  
Figure 5

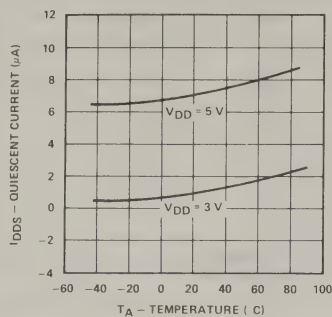


XTAL OUT  
Figure 6

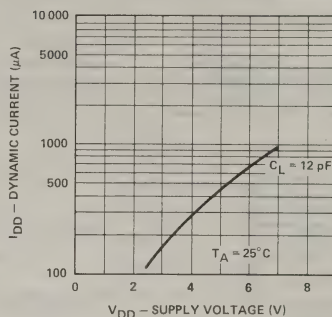
\*Circuit Protection Not Shown

# TYPICAL CHARACTERISTICS

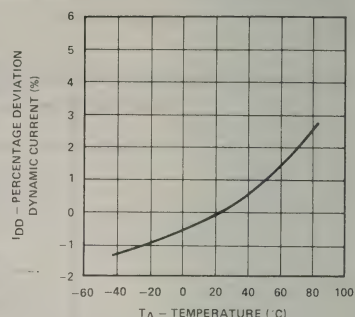
Typical Quiescent Current vs Temperature



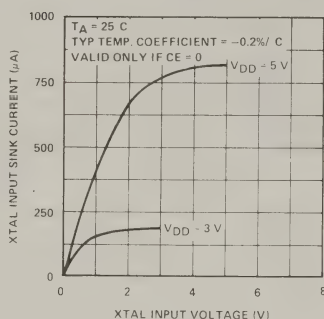
Typical Dynamic Current vs Supply Voltage



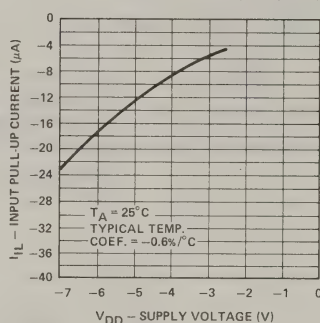
Typical Percentage Deviation of Dynamic Current vs Temperature (Normalized to 25°C)



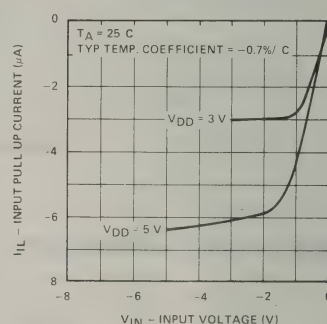
Typical XTAL IN Input Clamp Characteristics



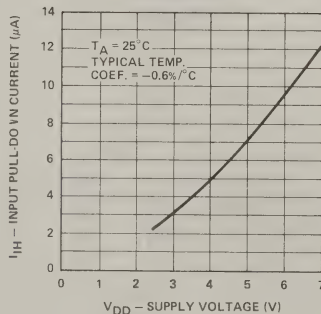
Typical Input Pull-Up Current vs Supply Voltage (X1, Y2, X3, Y1, Y2, Y3, Y4)



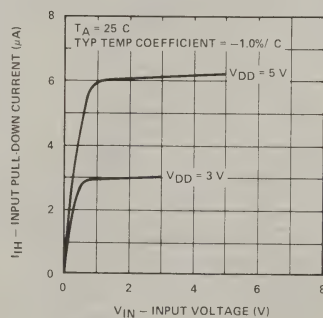
Typical Input Pull-Up Characteristics



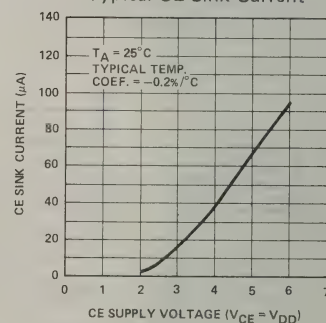
Typical Input Pull-Down Current vs Supply Voltage (M/S, FO1, FO2, Hold)



Typical Input Pull-Down Characteristics

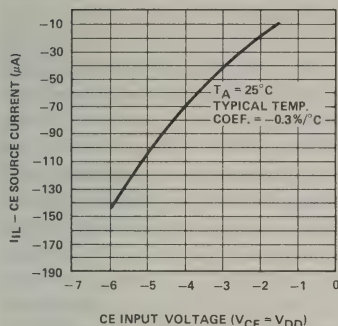


Typical CE Sink Current

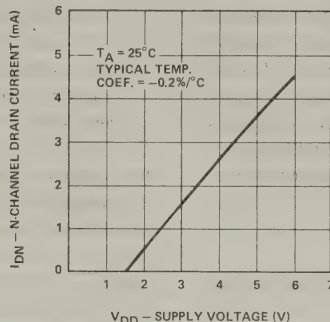


## TYPICAL CHARACTERISTICS (Cont'd)

Typical CE Source Current



Typical N-Channel Output Drain Characteristics (DP, M1, M2)



Typical P-Channel Output Drain Characteristics (DP, M1, M2)

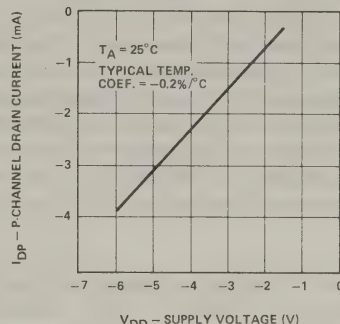


Table 1

PIN FUNCTION	DESCRIPTION																									
V <sub>DD</sub>	Positive voltage supply																									
DP	Dial Pulsing Output Buffer																									
M1	Mask 1 (Buffered Output) = Logic "1" during Dialing Sequence																									
M2	Mask 2 (Buffered Output) = Logic "1" during an Impulse																									
M/S	Mark/Space (Break/Make) Ratio select. On-chip active pull-down to V <sub>SS</sub> . <table><tr><td>O C</td><td>2:1</td></tr><tr><td>V<sub>DD</sub></td><td>3:2</td></tr></table> <p>Note: O C = Open circuit, see Figure 7</p>	O C	2:1	V <sub>DD</sub>	3:2																					
O C	2:1																									
V <sub>DD</sub>	3:2																									
F01, F02	Impulsing Rate Selection. On-chip active pull-down to V <sub>SS</sub> . <table><tr><th>F01</th><th>F02</th><th>Nominal Impulsing Rate</th><th>Actual* Impulsing Rate</th><th>System Clock Frequency</th></tr><tr><td>O C</td><td>O C</td><td>10 Hz</td><td>10.13 Hz</td><td>303.9 Hz</td></tr><tr><td>O C</td><td>V<sub>DD</sub></td><td>20 Hz</td><td>19.42 Hz</td><td>582.6 Hz</td></tr><tr><td>V<sub>DD</sub></td><td>O C</td><td>932 Hz</td><td>932.17 Hz</td><td>27,965.1 Hz</td></tr><tr><td>V<sub>DD</sub></td><td>V<sub>DD</sub></td><td>16 Hz</td><td>15.54 Hz</td><td>466.1 Hz</td></tr></table> <p>*Assumes f<sub>CLK</sub> = 3.579545 MHz</p>	F01	F02	Nominal Impulsing Rate	Actual* Impulsing Rate	System Clock Frequency	O C	O C	10 Hz	10.13 Hz	303.9 Hz	O C	V <sub>DD</sub>	20 Hz	19.42 Hz	582.6 Hz	V <sub>DD</sub>	O C	932 Hz	932.17 Hz	27,965.1 Hz	V <sub>DD</sub>	V <sub>DD</sub>	16 Hz	15.54 Hz	466.1 Hz
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V <sub>DD</sub>	V <sub>DD</sub>	16 Hz	15.54 Hz	466.1 Hz																						
CE	Chip Enable. Input/Output, left open it is internally controlled by keyboard decode logic. Can be externally forced for manually enabling chip.																									
XTAL IN	Crystal Input. Active, clamped low if CE = "0", high impedance if CE = "1".																									
XTAL OUT	Crystal Output. Buffer to drive crystal. Capacitive load on-chip.																									
V <sub>SS</sub>	System ground																									
X <sub>1</sub> , X <sub>2</sub> , X <sub>3</sub>	Column keyboard inputs having active pull-ups to V <sub>DD</sub> . Active LOW																									
Y <sub>1</sub> , Y <sub>2</sub> , Y <sub>3</sub> , Y <sub>4</sub>	Row keyboard inputs having active pull-ups to V <sub>DD</sub> . Active LOW																									
HOLD	Prevents further impulsing. On-chip active pull-down to V <sub>SS</sub> <table><tr><td>O C</td><td>Normal Operation</td></tr><tr><td>V<sub>DD</sub></td><td>No Impulsing. If activated during impulsing, hold occurs when the current digit is complete.</td></tr></table>	O C	Normal Operation	V <sub>DD</sub>	No Impulsing. If activated during impulsing, hold occurs when the current digit is complete.																					
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## FUNCTIONAL DESCRIPTION

**1.0 Clock Oscillator** — The on-chip oscillator amplifier is connected between the XTAL IN and XTAL OUT pins. The oscillator is completed by connecting a 3,579,545 Hz crystal in parallel with a 10M  $\Omega$  resistor between XTAL IN and XTAL OUT. When CE = "0" an N-channel transistor clamp is activated, disabling oscillator operation. On the transition of CE to logic "1" a fast oscillator turn-on circuit kicks XTAL IN voltage to the amplifier bias point allowing oscillator operation within 4 ms. The basic clock frequency of 3.58 MHz is predivided by a programmable counter to provide the chip system clock.

As an alternative, an LC oscillator can be formed as shown in Figure 15. Selection of  $f_{CLK} = 38.4$  kHz with F01 connected to  $V_{DD}$  will give an impulsing rate of 10 Hz.

It is also possible to control the DF320, DF320A, DF322 from an external clock applied to XTAL IN.

**2.0 Chip Enable, CE** — The Chip Enable pin is used to initialize the chip system. CE = "0" forces the chip into the static standby mode. In this mode the clock oscillator is OFF, internal registers are reset with the exception of the WRITE ADDRESS COUNTER and the circuit is ready to receive a new number or re-dial. While CE = "0" data cannot be received by the chip, but data previously entered and stored is maintained. When CE = "1" the clock oscillator is operating, the internal registers are enabled, and data can be entered from the keyboard up to a maximum of 20 digits.

CE is primarily controlled by a logic gate with function

$$F = \text{KEYBOARD INPUT} + M1 + \text{HOLD}$$

where + denotes logical OR.

To operate this gate, a resistor and capacitor should be connected in parallel between CE and  $V_{SS}$ . When the chip is used in the CE INTERNAL CONTROL MODE power ON reset occurs when  $V_{DD}$  is applied, since a logic "0" appears on the CE pin. The chip remains in the static standby condition until it receives the first valid keyboard input after  $V_{DD}$  is applied. This is statically decoded and causes CE = "1", hence enabling the clock oscillator. The debounce counter is then clocked by the system clock until the valid data condition is recognized. Data is then written into the on-chip RAM. CE is maintained at logic "1" by M1 during dialing.

The WRITE ADDRESS COUNTER is reset on recognition of the first valid debounced keyboard input provided that it is decoded during  $t_d$  of the pre-impulsing pause PIP (see Figure 8). In the CE INTERNAL CONTROL MODE this condition will always apply. When all keyed digits have been dialled, M1 goes to logic "0" and hence the chip returns to the static standby condition. If digits are sub-

sequently keyed during the same OFF-hook period, after a pause in dialling for example, the digit string will be recognized as a new number. This is not important provided RE-DIAL operation is not required.

The alternative to the CE INTERNAL CONTROL MODE is to override the internal logic gate with an externally derived signal. This mode of operation is referred to as the CE EXTERNAL CONTROL MODE. Figure 7 shows that if CE goes to logic "1" in the absence of a keyboard input, a single pulse of duration  $t_d$  is generated on M1. This pulse is intended to initialize a bistable latching relay used as shown in Figure 12. Immediately prior to M1 going to logic "1", the WRITE ADDRESS COUNTER is reset. All digits keyed subsequently are entered into consecutive RAM locations up to a maximum of 20. After the WRITE ADDRESS COUNTER has been reset, the RE-DIAL input code will not be recognized by the circuit. It is necessary that CE be maintained at logic "0"  $> 1 \mu s$  after  $V_{DD}$  is applied in order to ensure correct system initializing. If CE is linked to  $V_{DD}$  by the method shown in Figure 12, adequate delay is obtained.

**3.0 Data Entry** — Data is entered to the circuit via a double contact keyboard connected as shown in Figure 10. Keyboard inputs are active low and encoded as shown in Table 2.

Keyboard Code  
Table 2

No. of O/P Pulses	Digit	Y <sub>1</sub>	Y <sub>2</sub>	Y <sub>3</sub>	Y <sub>4</sub>	X <sub>1</sub>	X <sub>2</sub>	X <sub>3</sub>
1	1	0	1	1	1	0	1	1
2	2	0	1	1	1	1	0	1
3	3	0	1	1	1	1	1	0
4	4	1	0	1	1	0	1	1
5	5	1	0	1	1	1	0	1
6	6	1	0	1	1	1	1	0
7	7	1	1	0	1	0	1	1
8	8	1	1	0	1	1	0	1
9	9	1	1	0	1	1	1	0
10	0	1	1	1	0	1	0	1
RE-DIAL		1	1	1	0	1	1	0

NOTE: "0" indicates pin taken low.

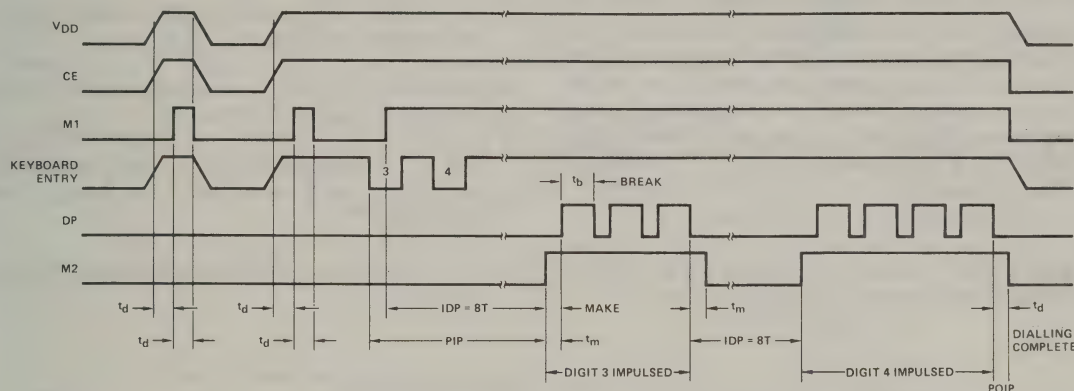
Keyboard inputs are fully decoded eliminating any possibility of invalid codes being recognized. A BCD format is used on-chip for data storage. Valid inputs have contact bounce removed via the debounce counter. Operation is illustrated in Figure 9. Input data is not written into the RAM until the input code has been present for a minimum of 3P and maximum of 4P (P = System Clock Period). The 1P uncertainty arises since data entry is not synchronized to the system clock. This is indicated by the shaded area on the keyboard entry waveform of Figure 9. The trailing edge of a keyboard entry is also debounced. The operation



of the debounce circuitry results in a maximum data entry rate of  $\text{SYS CLK} \div 9$ . Referring to Figure 9, data must remain stable during the RAM data entry period. Maximum contact bounce rejection is 10 ms at 10 Hz, 6.3 ms at 16 Hz or 5 ms at 20 Hz impulsing rates. Minimum data valid time is 16.7 ms at 10 Hz, 10.4 ms at 16 Hz or 8.4 ms at 20 Hz impulsing rates.

Upon recognition of the first keyboard input of a number string, the dial out sequence is initiated by a pre-impulsing pause (Figure 7). The WRITE ADDRESS COUNTER is

incremented on each digit entry. The contents of this counter indicate the length of the number to be dialed. The RE-DIAL code is recognized only if it is presented to the chip a maximum of 5P after  $\text{CE} = "1"$ . Decoding of RE-DIAL then inhibits the reset of the WRITE ADDRESS COUNTER, initiates the dialling sequence and the previous number string entered is dialed. If the circuit application is to utilize RE-DIAL, external CE control is necessary in some cases to ensure that  $\text{CE} = "1"$  from the first keyboard entry throughout dialling in order to ensure all digits entered are stored consecutively should a delay occur during dialling.

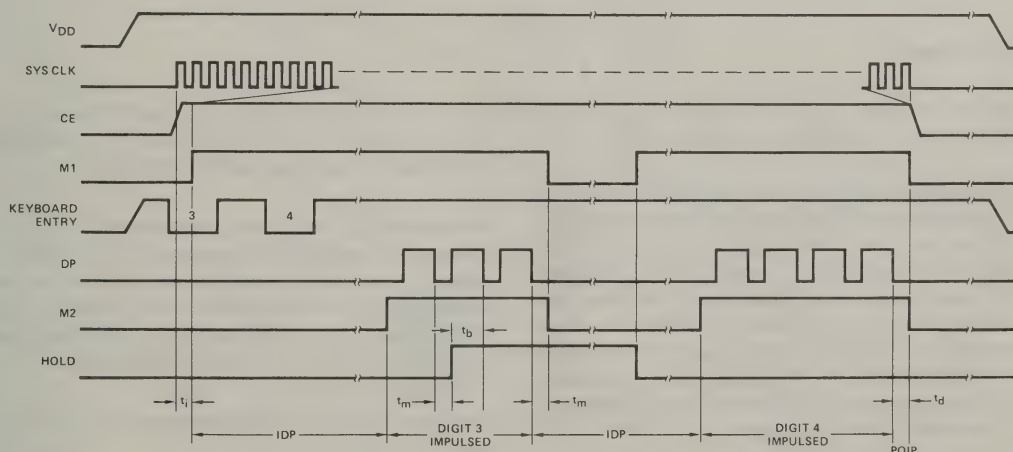


## NOTES:

- (1)  $t_d = 10 \times P$   
 $P = \text{System clock period} = T/30$   
 $T = \text{selected impulsing period}$
- (2) Pre-Impulsing Pause (PIP) =  $8T + t_d$
- (3) Post-Impulsing Pause (POIP) is equal to  $t_d$  ms on DF320, DF322 and 5T on DF320A.
- (4)  $t_b/t_m$  is the BREAK/MAKE RATIO.  $T = (t_m + t_b)$  ms.  
 $t_m = 10 \times P$  for 2:1 M/S ratio.  $t_m = 12 \times P$  for 3:2 M/S ratio.

Loop Disconnect Dialler Timing Diagram CE--External Control

Figure 7



## NOTE:

- (1)  $t_i = t_{ON} + t_d$  where  $t_{ON} = \text{Clock Start Up Time}$

Loop Disconnect Dialler Timing Diagram CE--Internal Control

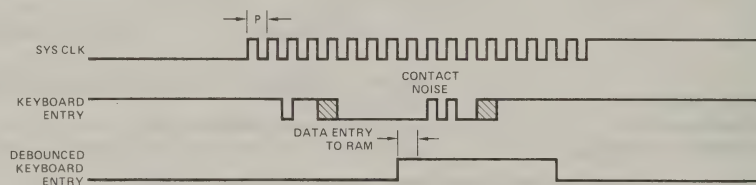
Figure 8

## FUNCTIONAL DESCRIPTION (Cont'd)

**4.0 Dialling Sequence** — The dialling or impulsing sequence is initiated on recognition of the first keyboard entry after  $CE = "1"$ . The dialling sequence is identical for both internal and external control of  $CE$ . (See Figure 7 and 8).

The basic impulsing pulse train is derived from the TIMING COUNTER AND DECODE. The IDP is timed by forcing a code on the OUTPUT COUNTER and inhibiting DP for the duration of IDP. The READ ADDRESS COUNTER then addresses the RAM and the first digit is used to program the decode of the OUTPUT COUNTER. A number of dial pulses is output via DP corresponding to the BCD data read from the RAM. At the completion of the digit, the READ ADDRESS COUNTER is incremented. The sequence continues until coincidence is recognized between the READ ADDRESS COUNTER contents and the WRITE ADDRESS COUNTER contents. The post-impulsing pause POIP, is then generated. The circuit then enters the dynamic standby condition if  $CE$  is maintained at logic "1" by external control, or the static standby condition if  $CE$  INTERNAL CONTROL MODE is used.

Impulsing rates, impulsing mark-to-space ratio and inter-digital pause are programmable as shown in Table 1.



Keyboard Input Debounce Timing Diagram  
Figure 9

## APPLICATIONS

The circuit of Figure 10 shows a method of connecting the DF320 in parallel with the telephone network.

When the handset is lifted and power applied to the circuit  $Q_2$  is fed base current through  $R_2$  which in turn drives  $Q_1$ .  $C_2$  is charged via  $R_3$  in series with  $D_1$  to  $(V_{Z1} - 0.7)V$ . When the minimum operating  $V_{DD}$  voltage is reached, power ON reset occurs via the  $CE$  network of  $C_1$  and  $R_8$ .  $Q_2$  is maintained in the ON condition by  $G_1$  while  $Q_3$ , and hence  $Q_4$ , are held OFF by  $G_2$ . The DF320 network appears in parallel with the telephone as an impedance  $> 10K \Omega$  in the standby condition with the telephone network connected in circuit through  $Q_1$ .

On recognition of the first keyed digit, the DF320 clock is started.  $M1$  then goes to logic "1" causing  $Q_2$ ,  $Q_1$  to turn OFF, and  $Q_3$ ,  $Q_4$  to turn ON. Hence the majority of the line loop current now flows through  $Q_4$ , and  $Z_1$ . When

The dialling sequence can be interrupted by applying logic "1" to HOLD. If  $HOLD = "1"$  is applied during dialling of a digit, the circuit does not enter the HOLD mode until the digit is complete. In the HOLD mode  $M1 = "0"$ , allowing the telephone line to be monitored. When HOLD is released dialling continues preceded by an IDP. (See Figure 8). HOLD is used to extend the IDP allowing intermediate dial tone recognition if RE-DIAL is used in a PABX for example. Operation can be manual or via external control logic as shown in Figure 13.

## NOTES:

- (1) The keyboard input decoding is mask programmable to suit different input codes.
- (2) The timing circuitry is mask programmable to give different M/S ratios and IDP values.
- (3) The clock predivision circuitry is mask programmable allowing use of different crystal or external clock frequencies.
- (4) The logic sense of DP, M1 and M2 outputs is mask programmable.

impulsing occurs  $Q_3$  and  $Q_4$  are turned OFF by DP acting on  $G_2$ . Line loop current is then reduced to approximately  $50 \mu A$  taken through  $R_2$ ,  $R_4$  and  $G_2$  in series.

When dialling is complete  $M1$  goes to logic "0" causing the telephone network to be reconnected. The DF320 then returns to the static standby condition. If the line loop is interrupted by the cradle switch during dialling, impulsing will continue until  $C_2$  discharges to a voltage such that  $R_8$  pulls  $CE$  to logic "0" causing the DF320 to reset.

The diode bridge protects the network from line polarity reversal.

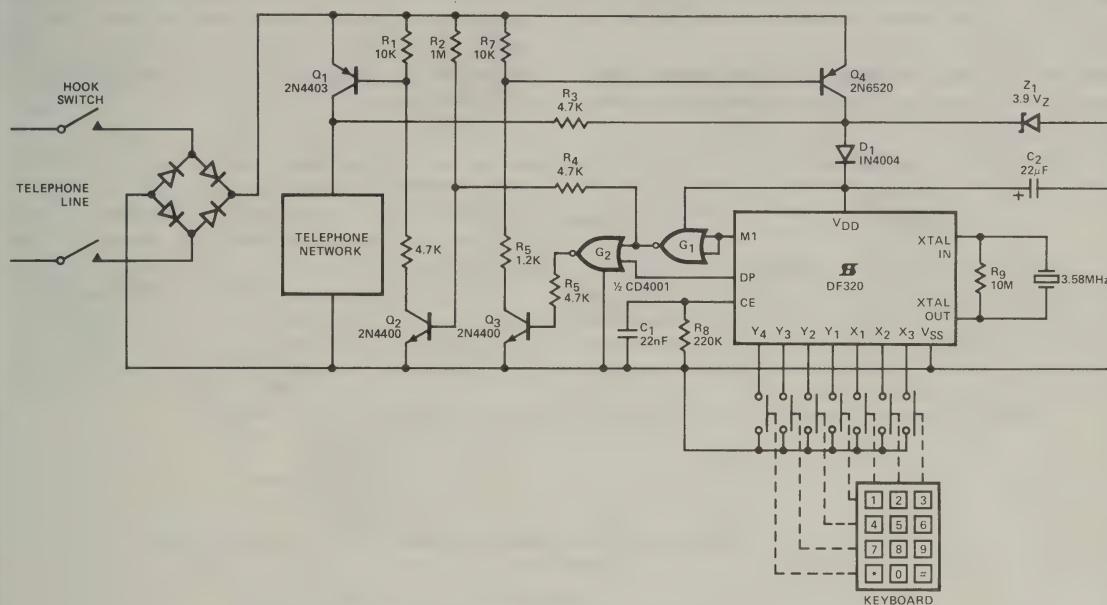
The circuit of Figure 11 shows a simple method of series connection of DF320 into the telephone set suitable for PABX or short line applications.

## APPLICATIONS (Cont'd)

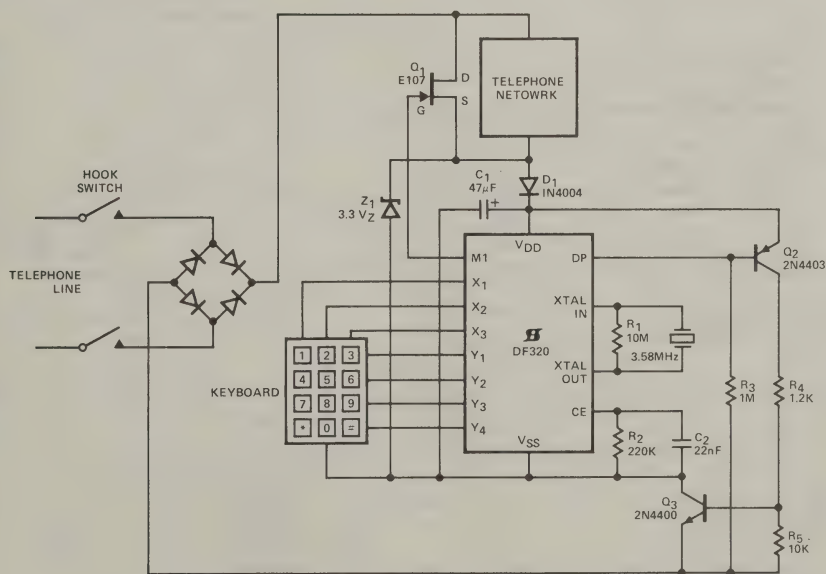
When the telephone handset is lifted, C<sub>1</sub> is charged via D<sub>1</sub> to (V<sub>Z1</sub> - 0.7) volts and DF320 power ON reset occurs. When the first keyed digit is recognized, M<sub>1</sub> goes to logic "1" muting the telephone network by switching on the low ON resistance JFET Q<sub>1</sub>, and maximizing the line loop current for impulsing. Impulsing occurs through DP switching Q<sub>2</sub>, and hence Q<sub>3</sub>, OFF. Rapid discharge of C<sub>1</sub> through Z<sub>1</sub> is prevented during line break by the blocking diode D<sub>1</sub>.

When dialling is complete the circuit returns to the static standby condition and Q<sub>1</sub> is switched OFF. Circuit reset during a line interruption by the cradle switch is as for the parallel connection mode.

If a requirement exists that no semiconductor components should appear in the telephone loop during normal speech, the circuit of Figure 12 is required.



DF320 Parallel Telephone Connection  
Figure 10



**DF320 Series Telephone Connection**  
**Figure 11**



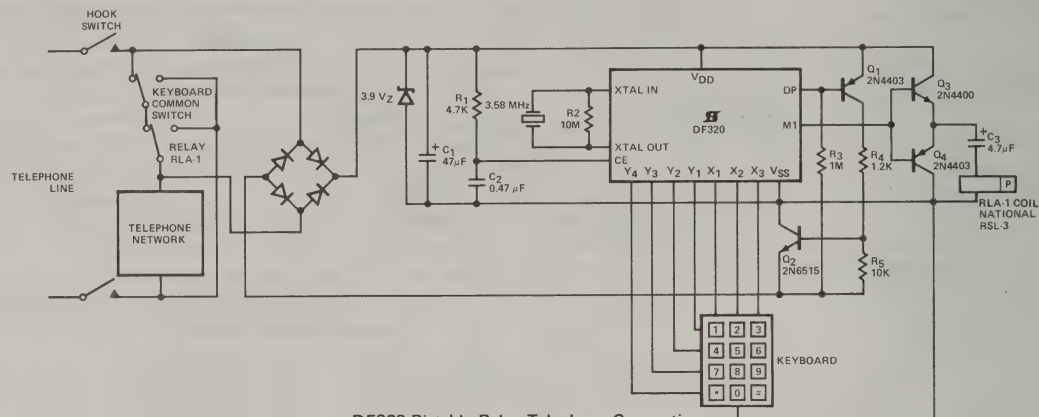
## APPLICATIONS (Cont'd)

While the circuits of Figures 10 and 11 did not require a common keyboard contact, it is necessary to have a common changeover switch in this case operating in conjunction with a bistable relay. In this application external control of CE is provided by the R<sub>1</sub>, C<sub>2</sub> network. If, when the handset is lifted, the relay contact is such that the DF320 network is connected in circuit, it is necessary to initialize this relay to reconnect the telephone network. This is achieved by the single pulse which occurs on M1 if CE goes to logic "1" in the absence of a keyboard input (Figure 7).

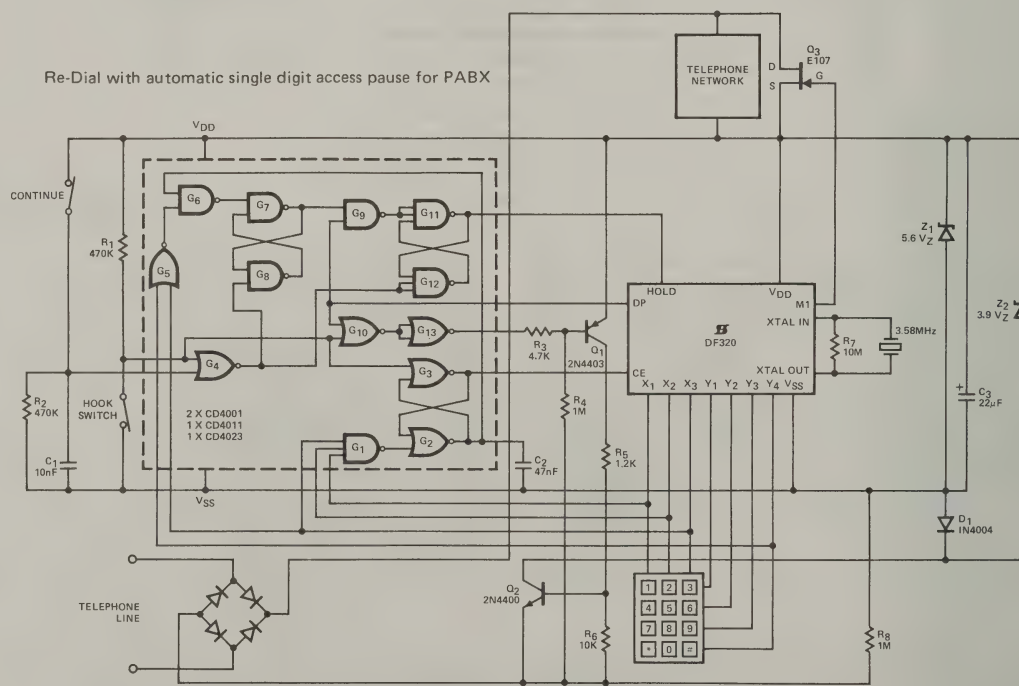
When the first digit is keyed, the DF320 network is connected into the telephone loop and the telephone network

short circuited by the keyboard common switch. M1 then goes to logic "1" switching the bistable relay hence maintaining the DF320 network in circuit. Impulsing occurs through DP switching Q<sub>1</sub> OFF which in turn switches Q<sub>2</sub>. When dialling is complete the bistable relay is pulsed, switching the telephone network back in circuit and short circuiting the DF320 network.

The circuit of Figure 13 shows additional gating circuitry to provide an automatic access pause after the first digit is dialed, by controlling HOLD. This is useful in PABX applications, eliminating the need for a manual hold facility if RE-DIAL is used.



**DF320 Bistable Relay Telephone Connection**  
**Figure 12**



**DF320 Series Telephone Connection**  
**Figure 13**



## APPLICATIONS (Cont'd)

The basic interface circuit is similar to that shown in Figure 11. Muting is achieved by Q<sub>3</sub> and line switching by Q<sub>2</sub> driven by Q<sub>1</sub>.

In the ON-hook condition, Q<sub>1</sub> is held OFF by G<sub>13</sub> and standby current is supplied to the DF320 network by R<sub>8</sub>; providing voltage limiting. CE is clamped to logic "0" by G<sub>3</sub>. The DF320 is in the static standby mode and the previously dialled number is stored.

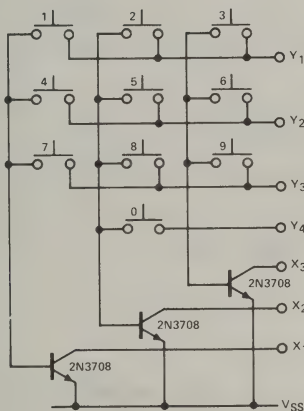
When the handset is lifted, G<sub>13</sub> goes to logic "0" switching Q<sub>1</sub>, and hence Q<sub>2</sub>, ON. The DF320 network V<sub>DD</sub> is now given by (V<sub>Z2</sub> - 0.7) volts. The DF320 remains in the static standby mode until the first key operation. G<sub>1</sub> decodes the common key function toggling the latch formed by G<sub>2</sub> and G<sub>3</sub> causing CE = "1". CE remains at logic "1" throughout the remainder of the OFF-hook condition ensuring that all digits keyed are stored by the DF320 as one number string. (See FUNCTIONAL DESCRIPTION, 3.0 DATA ENTRY).

If the first key operated is RE-DIAL, this condition is decoded by G<sub>5</sub>, and via G<sub>6</sub> sets the latch formed by G<sub>7</sub>

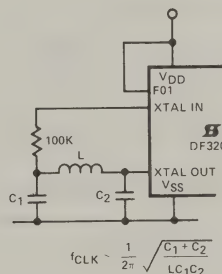
and G<sub>8</sub>. G<sub>9</sub> is enabled and the first dial pulse causes the latch formed by G<sub>11</sub> and G<sub>12</sub> to be set taking HOLD to logic "1". When the first digit is complete M1 goes to logic "0" enabling the telephone network. When dial tone is recognized the CONTINUE switch is operated causing HOLD = "0" by resetting the latches formed by G<sub>11</sub>, G<sub>12</sub> and G<sub>7</sub>, G<sub>8</sub>. The remainder of the number is then re-dialled. Subsequent operation of RE-DIAL is blocked by G<sub>6</sub>.

Figure 14 shows a simple method of interfacing a single contact matrix-type keyboard to the DF320. Operation of a key causes the on-chip pull-up transistor of the Y input to provide base drive current to the corresponding X input external bipolar transistor, which sinks the X input pull-up current through its collector. Hence, a valid code is presented.

As an alternative to the crystal oscillator it is possible to operate the DF320 from an LC combination connected as shown in Figure 15. F01 is connected to V<sub>DD</sub> selecting the 932 Hz impulsing condition. An oscillator frequency of 38.4kHz will give a 10 Hz impulsing rate.



Single Contact Keyboard Interface  
Figure 14



LC Oscillator  
Figure 15

# CMOS Loop Disconnect Dialer

## designed for . . .

- Push Button Telephones
- Repertory Dialers
- Telex
- Mobile Telephones
- Security and Fire Alert Systems
- Emergency Number Dialers

### DESCRIPTION

The DF328 monolithic CMOS Loop Disconnect Dialers each contain all the logic necessary to interface a standard double contact keyboard to a telephone system requiring loop disconnect signalling.

A dial pulsing output and muting output are provided to control the impulsing (loop disconnect) and muting functions. The circuit is capable of storing a number string of up to 20 digits and re-dialing this stored number automatically at a later time, initiated by a RE-DIAL input code. Impulsing mark/space ratio (M/S) and impulsing rate are pin programmable to meet most telephone requirements.

The use of Siliconix low voltage CMOS technology allows operation with an unregulated supply voltage down to a guaranteed minimum of 2.5 V. This feature, together with low operating current, negligible standby current and high noise immunity make the DF328 easy to interface from long telephone lines.

External component count is minimized by the inclusion of an on-chip clock oscillator, high impedance pull-down terminations to programming inputs as well as pull-up terminations to the keyboard giving direct interfacing.

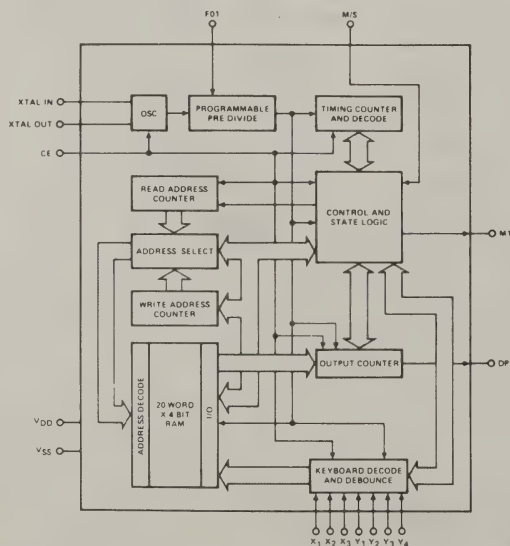
The DF328 provides the functions most commonly required in the push button telephone application. M1 is the muting output which remains at logic "1" throughout the dialing sequence.



### BENEFITS

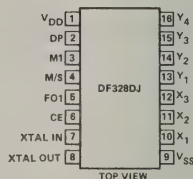
- Eliminates the Need for Regulated Supplies
  - 2.5 V to 5.5 V  $V_{DD}$  Range
- Minimizes Power Consumption
  - Standby Dissipation  $< 3 \mu W$
- Low Cost
  - Simple Support Circuitry
  - No External Power Up Reset Components
- Minimizes External Components
  - On-Chip Circuitry for: Keyboard Debouncing; Last Number Repeat; Input Termination
- Versatile
  - Selectable Mark/Space Ratio, Impulsing Speeds
  - Oscillator Uses Either LC Network or Crystal

### FUNCTIONAL BLOCK DIAGRAM



### PIN CONNECTION

#### DUAL-IN-LINE PACKAGE



ORDER NUMBER DF328DJ  
SEE PACKAGE 8

## ABSOLUTE MAXIMUM RATINGS

$V_{DD} - V_{SS}$  ..... -0.3 V to 8 V  
 Voltage on Any Pin .....  $V_{SS} - 0.3$  V to  $V_{DD} + 0.3$  V  
 Current at Any Pin ..... 10 mA  
 Operating Temperature ..... -40 to +85°C  
 Storage Temperature (J Package) ..... -65 to +125°C

Power Dissipation (J Package) \* ..... 450 mW

\*Derate 6.3 mW/°C above 25°C. All leads soldered to PC board.

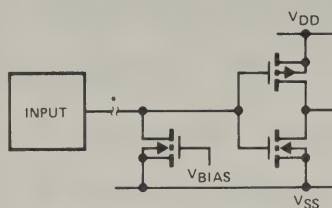
## ELECTRICAL CHARACTERISTICS

All voltages referenced to  $V_{SS}$  unless otherwise noted.

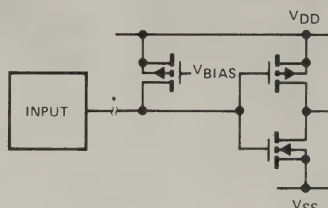
Characteristic				Min	Typ*	Max	Units	Test Conditions Unless Noted V <sub>DD</sub> = 3.0 V, T <sub>A</sub> = 25° C, f <sub>CLK</sub> = 3.579545 MHz		
1	S U P	V <sub>DD</sub>	Supply Voltage Operating Range	2.5		5.5	V			
2		I <sub>DSS</sub>	Standby Supply Current		1.0	15.0	μA	CE = V <sub>SS</sub>		
3		I <sub>DD</sub>	Operating Supply Current		180	250	μA	3.579545 MHz Crystal, C <sub>XTALOUT</sub> = 12 pF		
4	I N P U T	I <sub>IL</sub>	Pull-Up Transistor Source Current	-0.5	-3.0	-10.0	μA	V <sub>IN</sub> = V <sub>SS</sub>	X1, X2, X3,	
5		I <sub>IH</sub>	Input Leakage Current		0.1		nA	V <sub>IN</sub> = V <sub>DD</sub>	Y1, Y2, Y3, Y4	
6		I <sub>IL</sub>	Input Leakage Current		-0.1		nA	V <sub>IN</sub> = V <sub>SS</sub>	M/S F01	
7		I <sub>IH</sub>	Pull-Down Transistor Sink Current	0.5	3.0	10.0	μA	V <sub>IN</sub> = V <sub>DD</sub>		
8		V <sub>IL</sub>	Logic "0" Level			0.65	V	All Inputs		
9	V <sub>IH</sub>	Logic "1" Level	2.45			V				
10	O U T	V <sub>OL</sub>	Voltage Levels	Low Level		0	0.01	V	No Load  DP, M1	
11		V <sub>OH</sub>		High Level		2.99	3	V		
12		I <sub>OL</sub>	Drive Current	N-Channel Sink		0.5	2.0	mA		V <sub>OUT</sub> = 2.3 V
13		I <sub>OH</sub>		P-Channel Source		-0.5	-1.5	mA		V <sub>OUT</sub> = 0.7 V
14	D Y N A M I C	t <sub>r</sub>	Output Rise Time		1.0		μs	DP, M1 C <sub>L</sub> = 50 pF		
15		t <sub>f</sub>	Output Fall Time		1.0		μs			
16		f <sub>CLK</sub>	Clock Frequency	0.03		3.58	MHz			
17		M/S	Mark to Space Ratio		2:1			See Table 1		
18					3:2					
19		IDP	Interdigital Pause		8T		ms	T = Impulsing Period		
20		Impulsing Rate = 1/T			10		Hz	See Table 1		
21					932					
22		t <sub>ON</sub>	Clock Start Up Time		1.5	4	ms	Timed from CE = Logic "1"		
23		C <sub>IN</sub>	Input Capacitance		5.0		pF	Any Input		
24	POIP	Post Impulsing Pause		0.3T		ms	T = Selected Impulsing Period			

\*Typical parametric values are for Design Aid Only, not guaranteed and not subject to production testing. Timing waveforms are subject to production functional test.

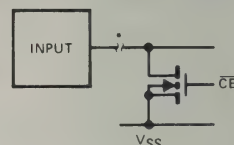
## INPUT OUTPUT SCHEMATICS



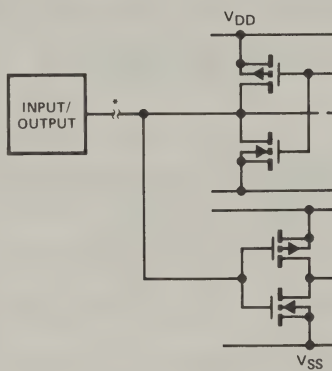
M/S, F01  
Figure 1



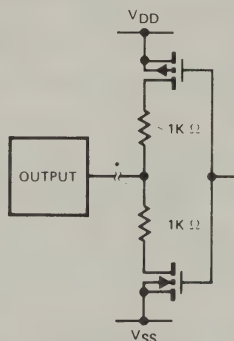
X<sub>1</sub>, X<sub>2</sub>, X<sub>3</sub>, Y<sub>1</sub>, Y<sub>2</sub>, Y<sub>3</sub>, Y<sub>4</sub>  
Figure 2



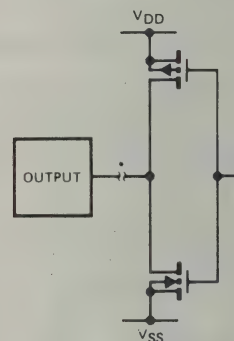
XTAL IN  
Figure 3



CE  
Figure 4



DP, M1  
Figure 5

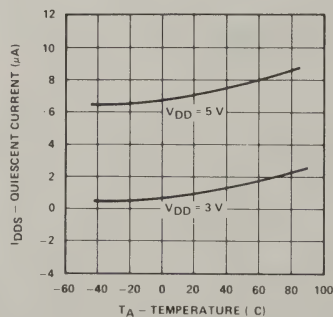


XTAL OUT  
Figure 6

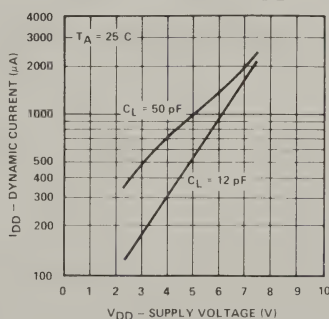
\*Circuit protection not shown

## TYPICAL CHARACTERISTICS

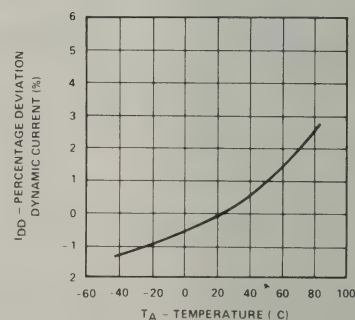
Typical Quiescent Current vs  
Temperature



Typical Dynamic Current vs  
Supply Voltage (V<sub>DD</sub>)

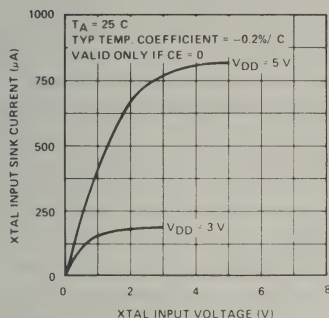


Typical Percentage Deviation  
of Dynamic Current vs  
Temperature (Normalized  
to 25°C)

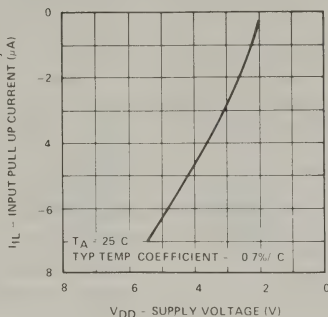




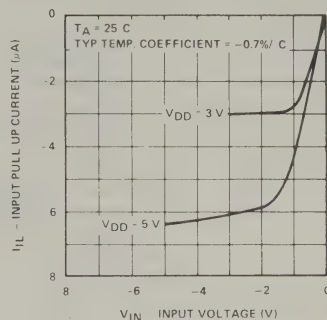
Typical XTAL IN Input Clamp Characteristics



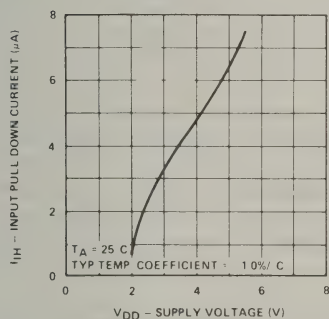
Typical Input Pull-Up Current vs Supply Voltage ( $X_1, X_2, X_3, Y_1, Y_2, Y_3, Y_4$ )



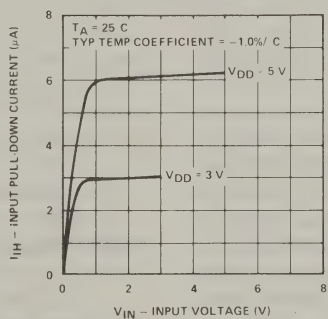
Typical Input Pull-Up Characteristics



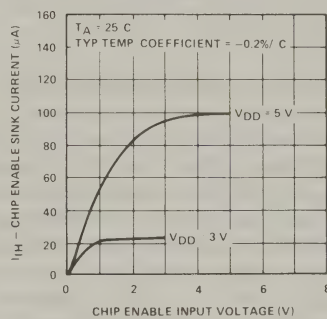
Typical Input Pull-Down Current vs Supply Voltage (M/S, F01)



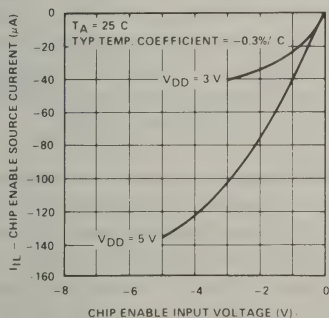
Typical Input Pull-Down Characteristics



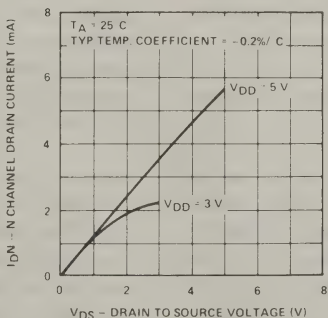
Typical Chip Enable Sink Characteristics



Typical Chip Enable Source Characteristics



Typical Output N-Channel Drain Characteristics (DP, M1)



Typical Output P-Channel Drain Characteristics (DP, M1)

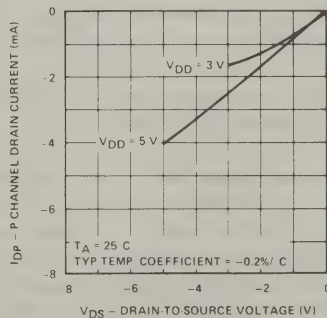


Table 1

PIN FUNCTION	DESCRIPTION												
V <sub>DD</sub>	Positive voltage supply												
DP	Dial Pulsing Output Buffer												
M1	Mask 1 (Buffered Output) = Logic "1" during Dialling Sequence												
M/S	Mark/Space (Break/Make) Ratio select. On-chip active pull-down to V <sub>SS</sub> . <table><tr><td>O/C</td><td>2 1</td></tr><tr><td>V<sub>DD</sub></td><td>3 2</td></tr></table> Note: O/C = Open circuit, see Figure 7.	O/C	2 1	V <sub>DD</sub>	3 2								
O/C	2 1												
V <sub>DD</sub>	3 2												
F01	Impulsing Rate Selection. On-chip active pull-down to V <sub>SS</sub> <table><tr><th>F01</th><th>Nominal Impulsing Rate</th><th>Actual* Impulsing Rate</th><th>System Clock Frequency</th></tr><tr><td>O/C</td><td>10 Hz</td><td>10.13 Hz</td><td>303.9 Hz</td></tr><tr><td>V<sub>DD</sub></td><td>932 Hz</td><td>932.17 Hz</td><td>27,965.1 Hz</td></tr></table> <p>* Assumes f<sub>CLK</sub> = 3.579545 MHz</p>	F01	Nominal Impulsing Rate	Actual* Impulsing Rate	System Clock Frequency	O/C	10 Hz	10.13 Hz	303.9 Hz	V <sub>DD</sub>	932 Hz	932.17 Hz	27,965.1 Hz
F01	Nominal Impulsing Rate	Actual* Impulsing Rate	System Clock Frequency										
O/C	10 Hz	10.13 Hz	303.9 Hz										
V <sub>DD</sub>	932 Hz	932.17 Hz	27,965.1 Hz										
CE	Chip Enable. Input/Output, left open it is internally controlled by keyboard decode logic. Can be externally forced for manually enabling chip												
XTAL IN	Crystal Input. Active, clamped low if CE = "0", high impedance if CE = "1".												
XTAL OUT	Crystal Output. Buffer to drive crystal. Capacitive load on-chip.												
V <sub>SS</sub>	System ground												
X1, X2, X3	Column keyboard inputs having active pull-ups to V <sub>DD</sub> . Active LOW.												
Y1, Y2, Y3, Y4	Row keyboard inputs having active pull-ups to V <sub>DD</sub> . Active LOW												

## FUNCTIONAL DESCRIPTION

**1.0 Clock Oscillator** — The on-chip oscillator amplifier is connected between the XTAL IN and XTAL OUT pins. The oscillator is completed by connecting a 3,579,545 Hz crystal in parallel with a 10M  $\Omega$  resistor between XTAL IN and XTAL OUT. When CE = "0" an N-channel transistor clamp is activated, disabling oscillator operation. On the transition of CE to logic "1" a fast oscillator turn-on circuit kicks XTAL IN voltage to the amplifier bias point allowing oscillator operation within 4 ms. The basic clock frequency of 3.58 MHz is predivided by a programmable counter to provide the chip system clock.

As an alternative, an LC oscillator can be formed as shown in Figure 14. Selection of  $f_{CLK} = 38.4$  kHz with F01 connected to V<sub>DD</sub> will give an impulsing rate of 10 Hz.

It is also possible to control the DF328 from an external clock applied to XTAL IN.

**2.0 Chip Enable, CE** — The Chip Enable pin is used to initialize the chip system. CE = "0" forces the chip into the static standby mode. In this mode the clock oscillator is OFF, internal registers are reset with the exception of the WRITE ADDRESS COUNTER and the circuit is ready to receive a new number or redial. While CE = "0" data cannot be received by the chip, but data previously entered and stored is maintained. When CE = "1" the clock oscillator is operating, the internal registers are enabled, and data can be entered from the keyboard up to a maximum of 20 digits.

CE is primarily controlled by a logic gate with function

$$F = \text{KEYBOARD INPUT} + M1$$

where + denotes logical OR.

To operate this gate, a resistor and capacitor should be connected in parallel between CE and V<sub>SS</sub>. When the chip is used in the CE INTERNAL CONTROL MODE power ON reset occurs when V<sub>DD</sub> is applied, since a logic "0" appears on the CE pin. The chip remains in the static standby condition until it receives the first keyboard input after V<sub>DD</sub> is applied. This is decoded and causes CE = "1", hence enabling the clock oscillator. The debounce counter is then clocked by the system clock until the valid data condition is recognized. Data is then written into the on-chip RAM. CE is maintained at logic "1" by M1 during dialling.

The WRITE ADDRESS COUNTER is reset on recognition of the first valid debounced keyboard input provided that it is decoded during  $t_d$  of the pre-impulsing pause PIP (see Figure 8). In the CE INTERNAL CONTROL MODE this condition will always apply. When all keyed digits have been dialled, M1 goes to logic "0" and hence the chip returns to the static standby condition. If digits are subsequently keyed during the same OFF-hook period, after a pause in dialling for example, the digit string will be recognized as a new number. This is not important provided RE-DIAL operation is not required.

## FUNCTIONAL DESCRIPTION (Cont'd)

The alternative to the CE INTERNAL CONTROL MODE is to override the internal logic gate with an externally derived signal. This mode of operation is referred to as the CE EXTERNAL CONTROL MODE. Figure 7 shows that if CE goes to logic "1" in the absence of a keyboard input, a single pulse of duration  $t_{td}$  is generated on M1. This pulse is intended to initialize a bistable latching relay used as shown in Figure 12. Immediately prior to M1 going to logic "1", the WRITE ADDRESS COUNTER is reset. All digits keyed subsequently are entered into consecutive RAM locations up to a maximum of 20. After the WRITE ADDRESS COUNTER has been reset, the RE-DIAL input code will not be recognized by the circuit. It is necessary that CE be maintained at logic "0"  $> 1 \mu s$  after  $V_{DD}$  is applied in order to ensure correct system initializing. If CE is linked to  $V_{DD}$  by the method shown in Figure 12, adequate delay is obtained.

**3.0 Data Entry** — Data is entered to the circuit via a double contact keyboard connected as shown in Figure 10. Keyboard inputs are active low and encoded as shown in Table 2.

Keyboard inputs are fully decoded eliminating any possibility of invalid codes being recognized. A BCD format is used on-chip for data storage. Valid inputs have contact bounce removed via the debounce counter. Operation is illustrated in Figure 9. Input data is not written into the RAM until the input code has been present for a minimum of 3P and maximum of 4P (P = System Clock Period). The 1P uncertainty arises since data entry is not synchronized to the system clock. This is indicated by the shaded area on the keyboard entry waveform of Figure 9. The trailing edge of a keyboard entry is also debounced. The operation of the debounce circuitry results in a maximum data entry rate of  $SYS CLK \div 9$ . Referring to Figure 9, data must remain stable during the RAM data entry period. Maximum

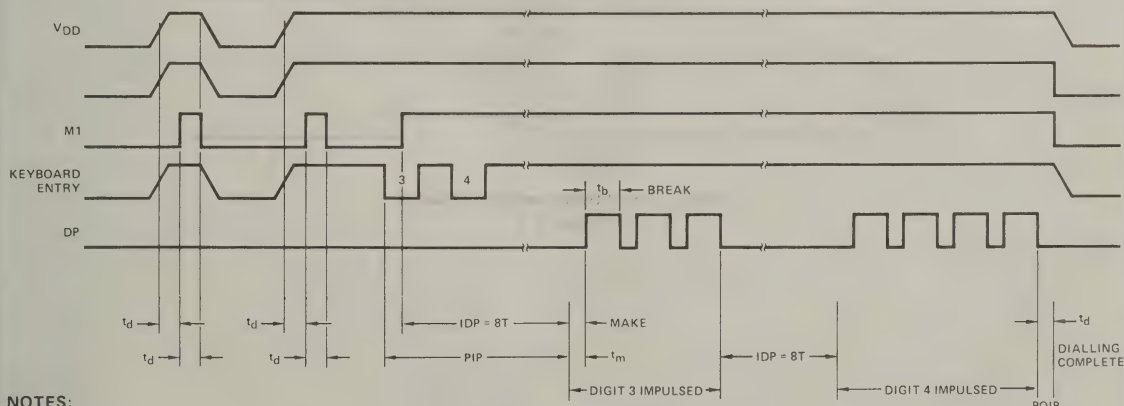
Keyboard Code  
Table 2

No. of O/P Pulses	Digit	Y <sub>1</sub>	Y <sub>2</sub>	Y <sub>3</sub>	Y <sub>4</sub>	X <sub>1</sub>	X <sub>2</sub>	X <sub>3</sub>
1	1	0	1	1	1	0	1	1
2	2	0	1	1	1	1	0	1
3	3	0	1	1	1	1	1	0
4	4	1	0	1	1	0	1	1
5	5	1	0	1	1	1	0	1
6	6	1	0	1	1	1	1	0
7	7	1	1	0	1	0	1	1
8	8	1	1	0	1	1	0	1
9	9	1	1	0	1	1	1	0
10	0	1	1	1	0	1	0	1
RE-DIAL		1	1	1	0	1	1	0

NOTE: "0" indicates pin taken low.

contact bounce rejection is 10 ms at 10 Hz impulsing rate. Minimum data valid time is 16.7 ms at 10 Hz impulsing rate.

Upon recognition of the first keyboard input of a number string, the dial out sequence is initiated by a pre-impulsing pause (Figure 7). The WRITE ADDRESS COUNTER is incremented on each digit entry. The contents of this counter indicate the length of the number to be dialled. The RE-DIAL code is recognized only if it is presented to the chip a maximum of 5P after CE = "1". Decoding of RE-DIAL then inhibits the reset of the WRITE ADDRESS COUNTER, initiates the dialling sequence and the previous number string entered is dialled. If the circuit application is to utilize RE-DIAL, external CE control is necessary in some cases to ensure that CE = "1" from the first keyboard entry throughout dialling in order to ensure all digits entered are stored consecutively should a delay occur during dialling.



## NOTES:

- (1)  $t_d = 10 \times P$   
P = System clock period =  $T/30$   
T is selected impulsing period
- (2) Pre-Impulsing Pause (PIP) =  $8T + t_d$
- (3) Post-Impulsing Pause (POIP) is equal to  $t_d$  ms
- (4)  $t_b/t_m$  is the BREAK/MAKE RATIO.  $T = (t_m + t_b)$  ms.  
 $t_m = 10 \times P$  for 2:1 M/S ratio.  $t_m = 12 \times P$  for 3:2 M/S ratio.

Loop Disconnect Dialler Timing Diagram CE—External Control

Figure 7

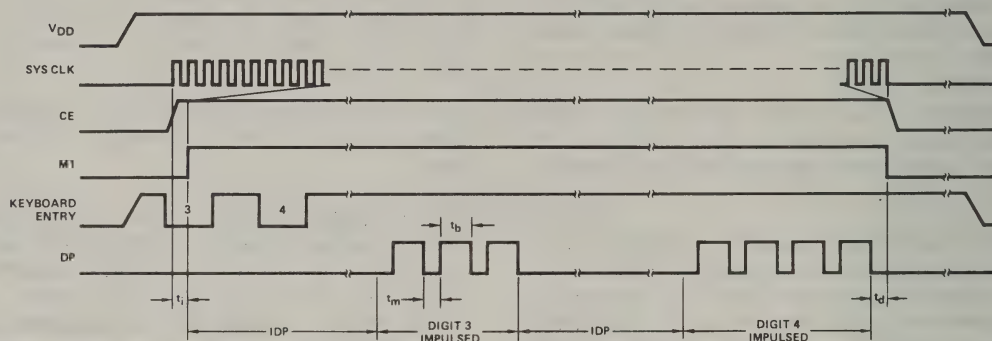


## FUNCTIONAL DESCRIPTION (Cont'd)

**4.0 Dialling Sequence** — The dialling or impulsing sequence is initiated on recognition of the first keyboard entry after  $CE = "1"$ . The dialling sequence is identical for both internal and external control of  $CE$ . (See Figures 7 and 8).

The basic impulsing pulse train is derived from the TIMING COUNTER AND DECODE. The IDP is timed by forcing a code on the OUTPUT COUNTER and inhibiting DP for the duration of IDP. The READ ADDRESS COUNTER then addresses the RAM and the first digit is used to program the

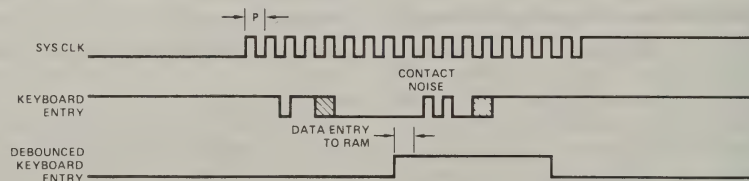
decode of the OUTPUT COUNTER. A number of dial pulses is output via DP corresponding to the BCD data read from the RAM. At the completion of the digit, the READ ADDRESS COUNTER is incremented. The sequence continues until coincidence is recognized between the READ ADDRESS COUNTER contents and the WRITE ADDRESS COUNTER contents. The post-impulsing pause POIP, is then generated. The circuit then enters the dynamic standby condition if  $CE$  is maintained at logic "1" by external control, or the static standby condition if  $CE$  INTERNAL CONTROL MODE is used.

**NOTE:**

(1)  $t_1 = t_{ON} + t_d$  where  $t_{ON}$  = Clock Start Up Time

Loop Disconnect Dialler Timing Diagram CE—Internal Control

Figure 8



Keyboard Input Debounce Timing Diagram

Figure 9



The circuit of Figure 10 uses a minimum number of components and provides very low current operation.

When the handset is lifted, power is applied through the diode bridge to the dialer circuit. Current flows through  $D_1$ ,  $CR_1$  and  $Z_2$ , establishing  $V_{DD}$  for the DF328 and charging  $C_1$ . When the minimum operating voltage ( $V_{DD}$ ) is reached, power on reset occurs via the CE network of  $C_2$  and  $R_1$ . Initially, both DP and M1 are LOW, giving a LOW at the gate of  $Q_1$  to hold it off, while the HIGH at the gate of  $Q_2$  turns it on, connecting the telephone network. The current limiting diode,  $CR_1$  serves two purposes. First, it limits the total dialer circuit current drawn from the loop to less than 1mA, and secondly, maintains a high dialer circuit shunting impedance across the telephone set network.  $Z_1$  is a high voltage, high surge capability device which provides protection against loop transients and office inductance spikes. The device should limit all transients to less than the breakdown voltages of  $CR_1$ ,  $Q_1$  and  $Q_2$  (100 volts).

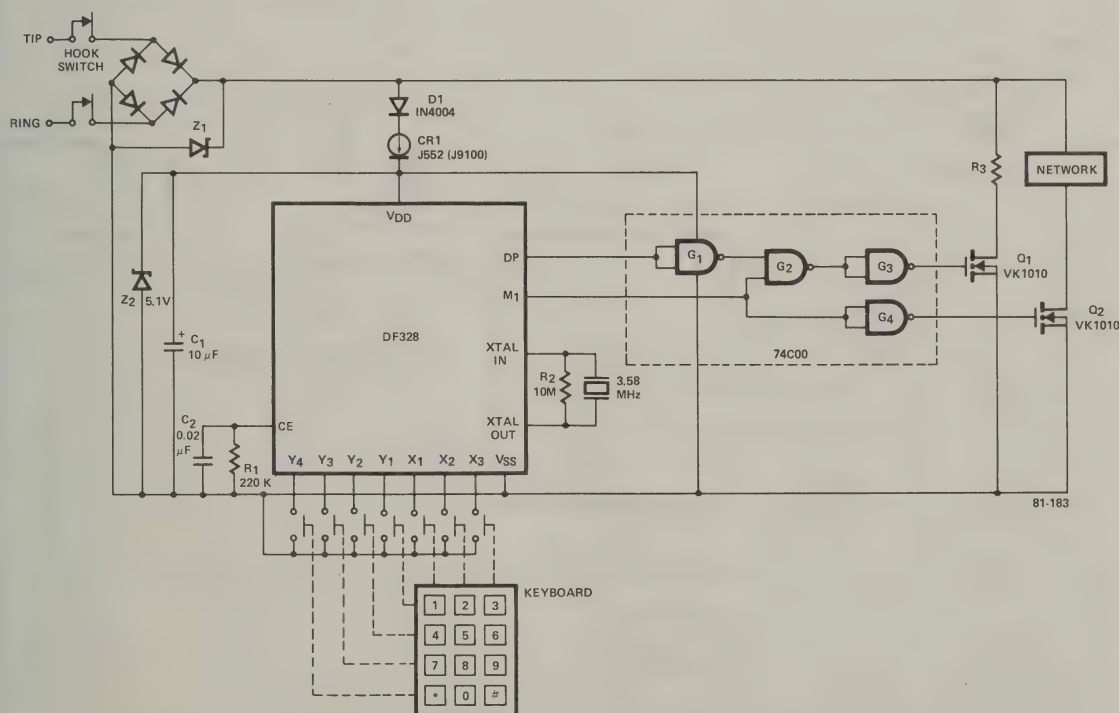
On recognition of the first keyed digit, the DF328 clock is started. M1 then goes HIGH, causing  $Q_2$  to turn off and  $Q_1$  to turn on. This mutes the receiver in the network and allows loop current flow to continue through  $R_3$  and  $Q_1$ . When dial pulse breaks occur, DP will go HIGH, causing  $Q_3$  output to go LOW and turning off  $Q_1$ . Loop current flow during breaks is controlled by  $CR_1$ .

When dialing is complete, M1 goes LOW causing  $Q_1$  to open and the telephone network to be reconnected. The DF328 then returns to the static standby condition and the oscillator is turned off.

The diode bridge protects the dialer circuit from line polarity reversal.  $D_1$  prevents rapid discharge of  $C_1$  during makes in dialing if the voltage across  $R_3$  and  $Q_1$  is lower than the voltage across  $C_1$ .

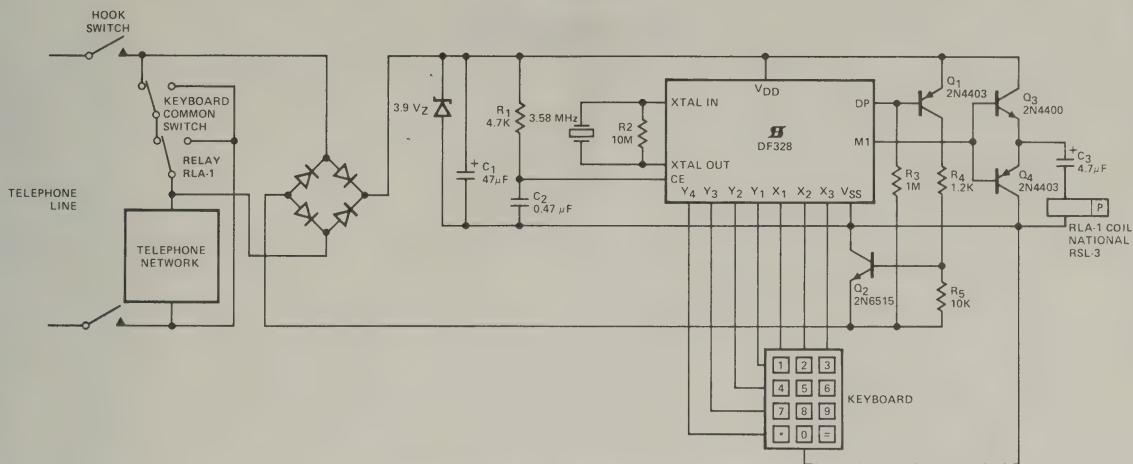
The VMOS devices combine low ON resistance and high breakdown voltage with very high input impedance. The high input impedance allows direct drive from CMOS logic and very low dialer circuit current consumption when compared to bipolar devices. This is important because of the wide variation in circuit operating conditions resulting from the need to accommodate both long and short loops.

Another approach is illustrated in Figure 11. The circuitry is similar to Figure 10 except for the dialing and muting functions. During non-dialing periods when the phone is off-hook, both DP and M1 will be LOW.  $Q_2$  will be held OFF by DP, allowing  $Q_1$  gate voltage to equal the drain voltage. A bias voltage will exist from gate to source, keeping it ON and allowing current flow through the telephone network.  $Q_3$  is also held OFF by M1. This in turn allows  $Q_4$  and  $Q_5$  to be ON. Since  $Q_5$  is in series with the receiver, no muting occurs.

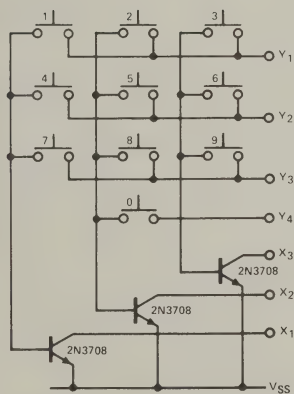


DF328 Dialer Circuit Connection  
Figure 10

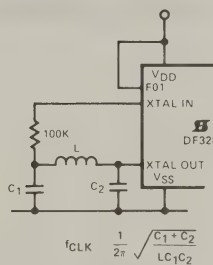




DF328 Bistable Relay Telephone Connection  
Figure 12



Single Contact Keyboard Interface  
Figure 13



LC Oscillator  
Figure 14







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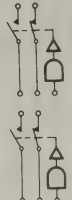


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*Stresses listed under "Absolute Maximum Ratings" may be applied (one at a time) to devices without resulting in permanent damage. This is a stress rating only and not subject to production testing. Exposure to absolute maximum rating conditions for extended periods may effect device reliability.*

# Analog Switches

Basic Part No. (Note 1)	Switch Type	Analog Voltage Range (V) (Note 4)	I <sub>DS(on)</sub> Max ( $\mu$ A) (Note 4)	I <sub>D(off)</sub> (nA)	Switching Time ( $\mu$ sec)		Logic Levels (V)		Opt. Supply Voltage (V)		Ref. Sup. V <sub>R</sub>	Comments	Switch Configuration	
					t <sub>ON</sub>	t <sub>OFF</sub>	V <sub>INL</sub>	V <sub>INH</sub>	(+) Sup. V <sub>+</sub>	(-) Sup. V <sub>-</sub>				Logic Sup. V <sub>L</sub>
TWO CHANNEL SPDT														
DG189	N-JFET	+ 10 to -12.5	10	10	0.3	0.25	0.8	2.0	10	-20	5	0	Break-Before-Make 15 V Supplies	
DG190	N-JFET	+ 15 to -7.5	10	10	0.3	0.25	0.8	2.0	15	-15	5	0	Break-Before-Make JAN/11107	
DG191	N-JFET	+ 10 to -12.5	30	1	0.15	0.13	0.8	2.0	10	-20	5	0	15 V Supplies	
DG191	N-JFET	+ 15 to -7.5	30	1	0.15	0.13	0.8	2.0	15	-15	5	0	Break-Before-Make JAN/11108	
DG191	N-JFET	+ 10 to -15	75	1	0.25	0.13	0.8	2.0	10	-20	5	0	15 V Supplies	
DG191	N-JFET	+ 15 to -10	75	1	0.25	0.13	0.8	2.0	15	-15	5	0	Make-Before-Break (DG191 Pin Out)	
DG243	Plus 40 CMOS	+ 15 to -15	50	1	0.5	1.0	0.8	2.0	15	-15	5	0	Break-Before-Make	
DG250	N-JFET	+ 15 to -7.5	300	0.2	0.15	0.13	0.8	2.0	15	-15	5	0	Low Power, TTL In	
DG303	CMOS	+ 15 to -15	50	1	0.3	0.25	0.8	4.0	15	-15	5	0	Low Power, CMOS In	
DG303A	Plus 40 CMOS	+ 15 to -15	50	1	0.3	0.25	0.8	4.0	15	-15	5	0	Low Power, CMOS In	
DG307	CMOS	+ 15 to -15	50	1	0.25	0.15	3.5	11.0	15	-15	5	0	Low Power, CMOS In	
DG307A	Plus 40 CMOS	+ 15 to -15	50	1	0.25	0.15	3.5	11.0	15	-15	5	0	Low Power, CMOS In	
DG390	CMOS	+ 15 to -15	50	1	0.3	0.25	0.8	4.0	15	-15	5	0	Low Power, DG190 Pin Out	
DG390A	Plus 40 CMOS	+ 15 to -15	50	1	0.3	0.25	0.8	4.0	15	-15	5	0	Low Power, DG190 Pin Out	
DG5043	CMOS	+ 15 to -15	50	1	1.0	0.5	0.8	2.0	15	-15	5	0	Low Power, DG190 Pin Out	
ONE CHANNEL DPST														
DG5044	CMOS	+ 15 to -15	50	1	1.0	0.5	0.8	2	15	-15	5	0	TTL Compatible	
TWO CHANNEL DPST														
DG183	N-JFET	+ 10 to -12.5	10	10	0.3	0.25	0.8	2.0	10	-20	5	0	Break-Before-Make	
DG184	N-JFET	+ 15 to -7.5	10	10	0.3	0.25	0.8	2.0	15	-15	5	0	15 V Supplies	
DG184	N-JFET	+ 10 to -12.5	30	1	0.15	0.13	0.8	2.0	10	-20	5	0	Break-Before-Make	
DG185	N-JFET	+ 15 to -7.5	30	1	0.15	0.13	0.8	2.0	15	-15	5	0	15 V Supplies	
DG185	N-JFET	+ 10 to -15	75	1	0.25	0.13	0.8	2.0	10	-20	5	0	Break-Before-Make	
DG185	N-JFET	+ 15 to -10	75	1	0.25	0.13	0.8	2.0	15	-15	5	0	15 V Supplies	
DG284	N-JFET	+ 15 to -7.5	300	0.2	0.15	0.13	0.8	2.0	15	-15	5	0	Break-Before-Make	
DG302	CMOS	+ 15 to -15	50	1	0.3	0.25	0.8	4.0	15	-15	5	0	Low Power, TTL In	
DG302A	Plus 40 CMOS	+ 15 to -15	50	1	0.3	0.25	0.8	4.0	15	-15	5	0	Low Power, CMOS In	
DG306	CMOS	+ 15 to -15	50	1	0.25	0.15	3.5	11.0	15	-15	5	0	Low Power, CMOS In	
DG306A	Plus 40 CMOS	+ 15 to -15	50	1	0.25	0.15	3.5	11.0	15	-15	5	0	Low Power, CMOS In	
DG384	CMOS	+ 15 to -15	50	1	0.3	0.25	0.8	4.0	15	-15	5	0	Low Power, DG184 Pin Out	
DG384A	Plus 40 CMOS	+ 15 to -15	50	1	0.3	0.25	0.8	4.0	15	-15	5	0	Low Power, DG184 Pin Out	
DG5045	CMOS	+ 15 to -15	50	1	1.0	0.5	0.8	2.0	15	-15	5	0	Low Power, DG184 Pin Out	

NOTES:

- The devices shown in **boldface** are recommended parts for new designs.
- The appropriate switching characteristic for multiplexers is **T<sub>TRANSITION</sub>**; not **t<sub>ON</sub>**, **t<sub>OFF</sub>**.
- V<sub>REF</sub> = 15 V. The appropriate switching characteristic for multiplexers is **T<sub>TRANSITION</sub>**; not **t<sub>ON</sub>**, **t<sub>OFF</sub>**.
- Analog voltage range is a function of supply voltages. Where a FET switch is PMOS or CMOS, **V<sub>DS</sub>** is also a function of Supply Voltage and Analog Voltage. See individual data sheets for more detail. Values shown are for temperature suffix A.
- Device normally operates with resistor to +10 V.

# Analog Switches (Cont'd)

Basic Part No. (Note 1)	Switch Type	Analog Voltage Range (V) (Note 4)	I <sub>DS(on)</sub> Max (μA) (Note 4)	I <sub>O(off)</sub> (mA)	Switching Time (μsec)	Logic Levels (V)		Opt. Supply Voltage (V)		Ref. Sup. V <sub>R</sub>	Comments	Switch Configuration		
						V <sub>INL</sub>	V <sub>INH</sub>	(+) Sup. V <sub>+</sub>	(-) Sup. V <sub>-</sub>					
SINGLE CHANNEL SPST														
DG5040	Plus 40 CMOS	+15 to -15	50	1	1.0	0.5	0.8	2	15	-15	5	—	TTL Compatible	1 SPST Switch per Package
TWO CHANNEL SPST														
DG180	N-JFET	+10 to -12.5	10	10	0.3	0.25	0.8	2.0	10	-20	5	0	Break-Before-Make	2 SPST Switches per Package
DG181	N-JFET	+10 to -12.5	10	10	0.3	0.26	0.8	2.0	15	-15	5	0	15 V Supplies	
DG182	N-JFET	+10 to -12.5	30	1	0.15	0.13	0.8	2.0	10	-20	5	0	Break-Before-Make	
DG182	N-JFET	+10 to -15	75	1	0.25	0.13	0.8	2.0	15	-15	5	0	15 V Supplies JAN/11101	
DG200	N-JFET	+10 to -15	75	1	0.25	0.13	0.8	2.0	10	-20	5	0	Break-Before-Make	
DG200	CMOS	+10 to -15	70	2	1.0	0.5	0.8	2.4	15	-15	—	(Note 3)	15 V Supplies JAN/11102	
DG200A	Plus 40 CMOS	+15 to -15	70	2	1.0	0.5	0.8	2.4	15	-15	—	—	JAN/12303	
DG281	N-JFET	+15 to -15	300	0.2	0.15	0.13	0.8	2.0	15	-15	5	0	Low Charge Injection	
DG300	CMOS	+15 to -15	50	1	0.3	0.25	0.8	4.0	15	-15	—	—	Low Power, TTL In	
DG300A	Plus 40 CMOS	+15 to -15	50	1	0.3	0.25	0.8	4.0	15	-15	—	—	Low Power, TTL In	
DG304	CMOS	+15 to -15	50	1	0.25	0.15	3.5	11.0	15	-15	—	—	Low Power, CMOS In	4 SPST Switches per Package
DG304A	Plus 40 CMOS	+15 to -15	50	1	0.25	0.15	3.5	11.0	15	-15	—	—	Low Power, CMOS In	
DG381	CMOS	+15 to -15	50	1	0.3	0.25	0.8	4.0	15	-15	—	—	Low Power, DG181 Pin Out	
DG381A	Plus 40 CMOS	+15 to -15	50	1	0.3	0.25	0.8	4.0	15	-15	—	—	Low Power, DG181 Pin Out	
DG5041	Plus 40 CMOS	+15 to -15	50	1	1.0	0.5	0.8	2.0	15	-15	5	—	TTL Compatible	
FOUR CHANNEL SPST														
DG201	CMOS	+15 to -15	175	1	1.0	0.5	0.8	2.4	15	-15	—	(Note 3)	JAN/12304	4 SPST Switches per Package
DG201A	Plus 40 CMOS	+15 to -15	175	1	1.0	0.5	0.8	2.4	15	-15	—	—	TTL In	
DG212	Plus 40 CMOS	+15 to -15	175	5	0.5	0.8	0.8	2.4	15	-15	5	—	Low Cost, TTL In	
DG212	Plus 40 CMOS	+15 to -15	175	5	0.5	0.8	0.8	2.4	15	-15	5	—	Low Cost, TTL In	
DG306	CMOS	+15 to -15	100	1	0.2	0.15	3.5	11.0	15	-15	—	—	Low Cost CMOS In	
DG309	Plus 40 CMOS	+15 to -15	100	5	0.2	0.15	3.5	11.0	15	-15	—	—	Low Cost CMOS In	
ONE CHANNEL SPDT														
DG186	N-JFET	+10 to -12.5	10	10	0.3	0.25	0.8	2.0	10	-20	5	0	Break-Before-Make	1 SPST Switch per Package
DG187	N-JFET	+15 to -7.5	10	10	0.3	0.25	0.8	2.0	15	-15	5	0	15 V Supplies	
DG187	N-JFET	+10 to -12.5	30	1	0.15	0.13	0.8	2.0	10	-20	5	0	Break-Before-Make	
DG188	N-JFET	+15 to -7.5	30	1	0.15	0.13	0.8	2.0	15	-15	5	0	15 V Supplies JAN/11105	
DG188	N-JFET	+10 to -15	75	1	0.25	0.13	0.8	2.0	10	-20	5	0	Break-Before-Make	
DG287	N-JFET	+15 to -10	75	1	0.25	0.13	0.8	2.0	15	-15	5	0	15 V Supplies JAN/11106	
DG287	N-JFET	+10 to -7.5	300	0.2	0.15	0.13	0.8	2.0	15	-15	5	0	Break-Before-Make	
DG301	CMOS	+15 to -15	50	1	0.3	0.25	0.8	4.0	15	-15	—	—	Low Power, TTL In JAN/11602	
DG301A	Plus 40 CMOS	+15 to -15	50	1	0.3	0.25	0.8	4.0	15	-15	—	—	Low Power, CMOS In	
DG305	CMOS	+15 to -15	50	1	0.25	0.15	3.5	11.0	15	-15	—	—	Low Power, CMOS In	
DG305A	Plus 40 CMOS	+15 to -15	50	1	0.25	0.15	3.5	11.0	15	-15	—	—	Low Power, CMOS In	
DG387	CMOS	+15 to -15	50	1	0.3	0.25	0.8	4.0	15	-15	—	—	Low Power, DG187 Pin Out	
DG387A	Plus 40 CMOS	+15 to -15	50	1	0.3	0.25	0.8	4.0	15	-15	—	—	Low Power, DG187 Pin Out	
DG5042	CMOS	+15 to -15	50	1	1.0	0.5	0.8	2.0	15	-15	5	—	TTL Compatible	

## NOTES:

- The devices shown in **boldface** are recommended parts for new designs.
- The appropriate switching characteristic for multiplexers is 'TRANSITION', not 'ON', 'OFF'.
- $V_{REF} = 1.5$  V is used when supply voltages  $< \pm 15$  V are used. Not needed when supply voltages of  $\pm 15$  V are used.
- Analog voltage range is a function of supply voltages. Where a FET switch is PMOS or CMOS,  $V_{DS}$  is also a function of Supply Voltage and Analog Voltage. See individual data sheets for more detail. Values shown are for temperature suffix A.
- Device normally operates with resistor to  $+10$  V.



# 5-Channel SPST PMOS Switches with Drivers

## designed for . . .

**Siliconix**

**DG123**

- Communication Systems
- Portable, Battery Operated Units
- Make-Before-Break Switching  
i.e. Feedback Resistor Switching  
in Variable Gain Op-Amps

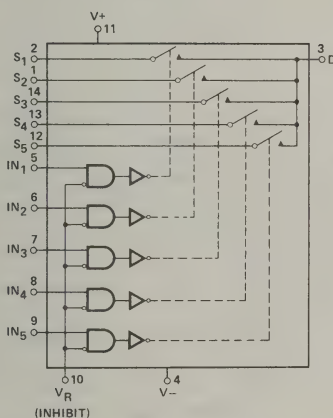
### BENEFITS

- Minimizes Standby Power Requirements
  - 550  $\mu$ W
- Low Leakage
  - $\leq 1$  nA
- Reduces External Component Requirements
  - Internal Zener Diodes Protect All MOS Gates

### DESCRIPTION

The DG123 contains five MOS field-effect transistors designed to function as electronic switches. Level-shifting drivers enable a low-level input (0.4 to 1.3 V) to control the ON-OFF condition of each switch. In the ON state each switch conducts current equally well in either direction, and in the OFF state the switches will block voltages up to 20 V peak-to-peak. In the OFF state, total circuit power dissipation is  $< 0.5$  mW. Positive logic "1" at the input turns the switch ON. Switch action is make-before-break. Not recommended for new designs.

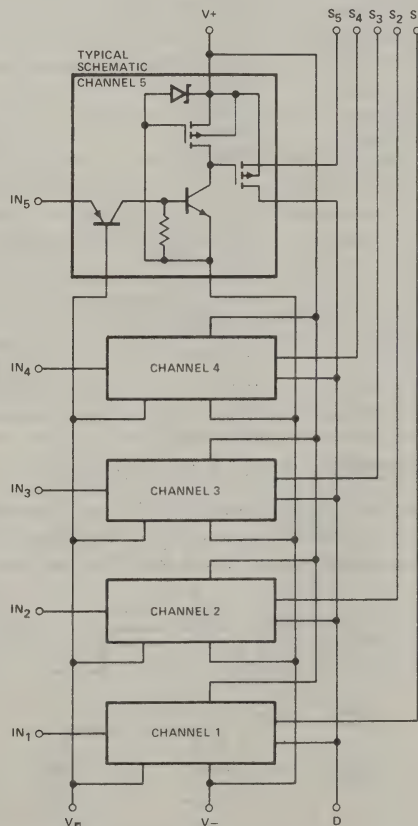
### FUNCTIONAL DIAGRAM



LOGIC	SWITCH
0	ON
1	OFF

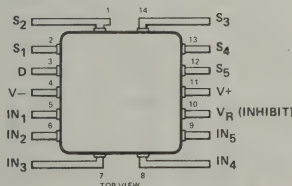
SWITCHES CLOSED FOR LOGIC "1" INPUT  
(POSITIVE LOGIC)

### SCHEMATIC DIAGRAM



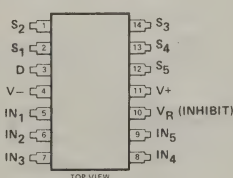
### PIN CONFIGURATIONS

#### Flat Package



ORDER NUMBER:  
DG123AL  
SEE PACKAGE 5

#### Dual-In-Line Package



ORDER NUMBERS:  
DG123AP OR DG123BP  
SEE PACKAGE 11

**Analog Switches**

# ABSOLUTE MAXIMUM RATINGS

V <sub>+</sub> to V <sub>-</sub>	36 V
V <sub>D</sub> to V <sub>-</sub>	36 V
V <sub>S</sub> to V <sub>-</sub>	36 V
V <sub>D</sub> to V <sub>S</sub>	25 V
V <sub>S</sub> to V <sub>D</sub>	25 V
V <sub>R</sub> to V <sub>-</sub>	30 V
V <sub>IN</sub> to V <sub>-</sub>	30 V
V <sub>R</sub> to V <sub>IN</sub>	6 V
V <sub>IN</sub> to V <sub>R</sub>	2 V

Current (Any Terminal)	30 mA
Storage Temperature	-65 to 150°C
Operating Temperature (A Suffix)	-55 to 125°C
(B Suffix)	-20 to 85°C
Power Dissipation*	
Flat Package**	750 mW
14 Pin DIP***	825 mW

\*All leads soldered or welded to PC board.

\*\*Derate 10 mW/°C above 75°C.

\*\*\*Derate 11 mW/°C above 75°C.

# ELECTRICAL CHARACTERISTICS

All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

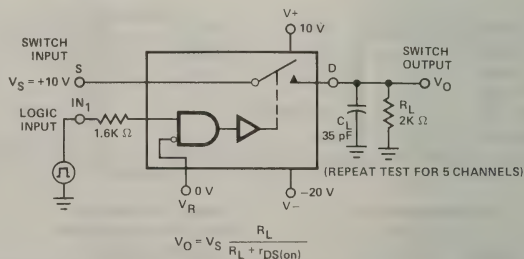
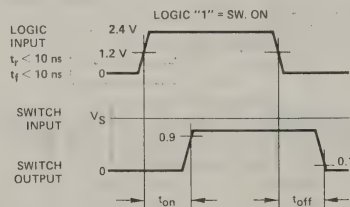
CHARACTERISTIC			MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V+ = 10 V, V- = -20 V, VR = 0	
			A SUFFIX			B SUFFIX					
			-55°C	25°C	125°C	-20°C	25°C	85°C			
1	SDWITCHING	rDS(on) Drain-Source ON Resistance	100	100	125	125	125	150	Ω	V <sub>D</sub> = 10 V	IS = -1 mA, IIN = 1 mA
2			200	200	250	225	225	300		V <sub>D</sub> = 0	
3			450	450	600	500	500	600		V <sub>D</sub> = -10 V	
4	TCH	IS(off) Source OFF Leakage Current		-1	-1000		-5	-100	nA	VS = -10 V, VD = 10 V	VIN = 0.4 V
5		ID(off) Drain OFF Leakage Current		-1	4000		-10	-300		VD = -10 V, VS = 10 V	
6		ID(on) + IS(on) Channel ON Leakage Current		4	4000		10	300		VD = VS = 10 V	
7	IN	IINL Logic Input Current, Input Voltage Low	1	1	100	5	5	100	μA	VIN = 0.4 V	
8		VINH Input Voltage, High	1.3	1	0.8	1.3	1	1	V	IIN = 1 mA	
9		ton Turn-ON Time		0.3			0.5		μs	See Switching Time Test Circuit	
10	toff Turn-OFF Time		2			2					
11	NAC	CS(off) Source OFF Capacitance		3 Typ*			3 Typ*		pF	VS = 0, ID = 0	f = 1 MHz
12		CD(off) Drain OFF Capacitance		7 Typ*			7 Typ*			VD = 0, IS = 0	
13	Off Isolation		Typ > -50 dB at 5 MHz*							RL = 100Ω, CL = 3 pF	
14	SUPPLY	I+ Positive Supply Current		3			3		mA	IIN = 1 mA, One Channel ON	
15		I- Negative Supply Current		-6			-6				
16		IR Reference Supply Current		-0.5			-0.5				
17		I+ Positive Supply Current		15			25		μA	VIN = 0.4 V, All Channels OFF	
18		I- Negative Supply Current		-20			-40				
19	IR Reference Supply Current		-10			-20					

\*Typical Values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

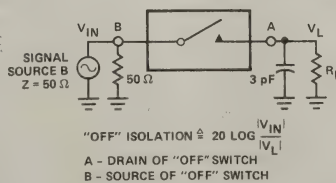
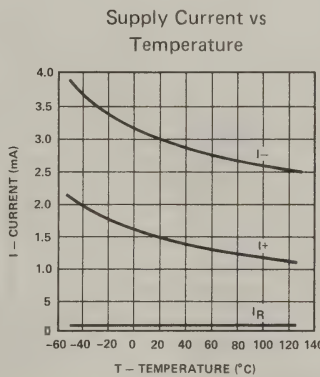
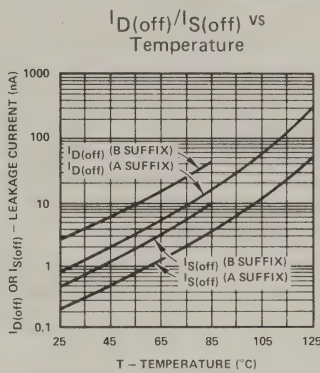
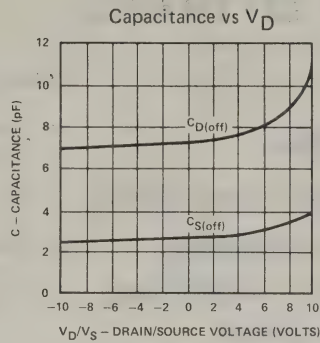
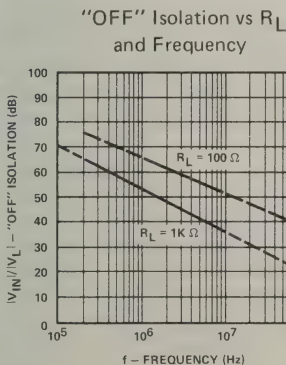
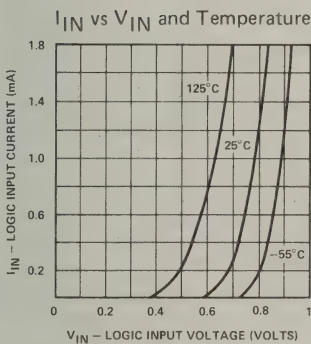
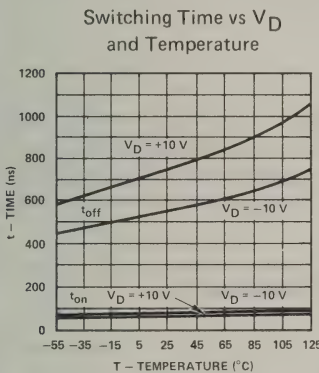
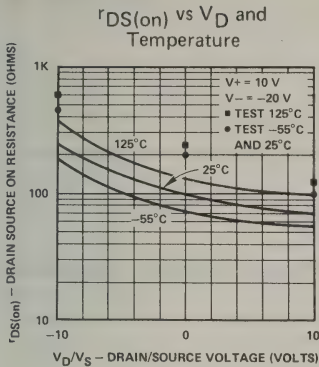
IBAF-A + MABA

# SWITCHING TIME TEST CIRCUIT

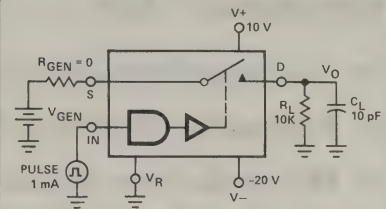
Switch output waveform shown for V<sub>S</sub> = constant with logic input waveform as shown. Note that V<sub>S</sub> may be + or - as per switching time test circuit. V<sub>O</sub> is the steady state output with switch on. Feedthrough via gate capacitance may result in spikes at leading and trailing edge of output waveform.



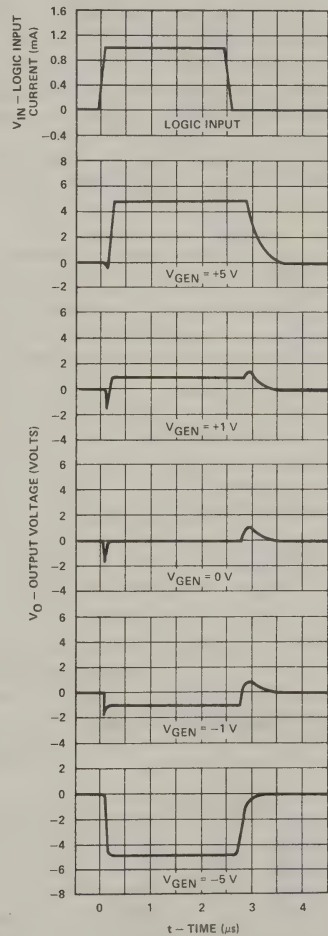
# TYPICAL CHARACTERISTICS



Typical delay, rise, fall, settling times, and switching transients in this circuit.



If  $R_{GEN}$ ,  $R_L$  or  $C_L$  is increased, there will be proportional increases in rise and/or fall RC times.





# 5-Channel SPST PMOS Switches with Drivers



*designed for . . .*

- **Communication Systems**
- **Portable, Battery Operated Units**
- **Make-Before-Break Switching  
i.e. Feedback Resistor Switching  
in Variable Gain Op-Amps**

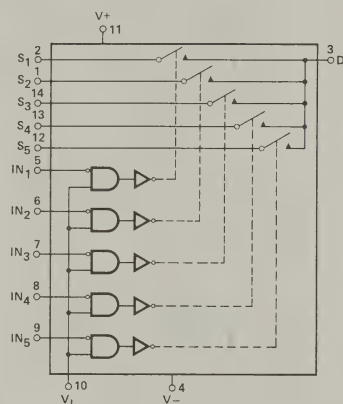
## BENEFITS

- **Minimizes Standby Power Requirements**
  - 550  $\mu$ W
- **Low Leakage**
  - $\leq 1$  nA
- **Reduces External Component Requirements**
  - Internal Zener Diodes Protect All MOS Gates

## DESCRIPTION

The DG125 contains five MOS field-effect transistors designed to function as electronic switches. Level-shifting drivers enable a low-level input (0.4 to 5 V) to control the ON-OFF condition of each switch. In the ON state each switch conducts current equally well in either direction, and in the OFF state the switches will block voltages up to 20 V peak-to-peak. In the OFF state, total circuit power dissipation is  $< 0.5$  mW. Positive logic "1" at the input turns the switch OFF. Switch action is make-before-break. Not recommended for new designs.

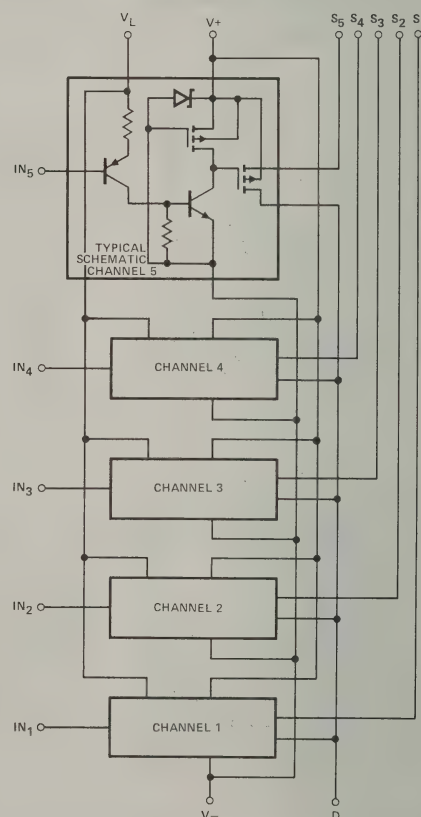
## FUNCTIONAL DIAGRAM



LOGIC	SWITCH
0	ON
1	OFF

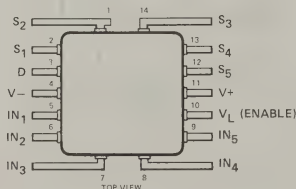
SWITCH STATES ARE FOR LOGIC "1" INPUT  
(POSITIVE LOGIC)

## SCHEMATIC DIAGRAM



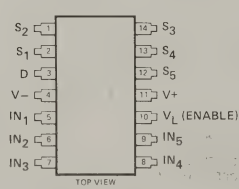
## PIN CONFIGURATIONS

### Flat Package



ORDER NUMBER: DG125AL  
SEE PACKAGE 5

### Dual-In-Line Package



ORDER NUMBERS:  
DG125AP OR DG125BP  
SEE PACKAGE 11



## ABSOLUTE MAXIMUM RATINGS

V <sub>+</sub> to V <sub>-</sub>	36 V
V <sub>D</sub> to V <sub>-</sub>	36 V
V <sub>S</sub> to V <sub>-</sub>	36 V
V <sub>D</sub> to V <sub>S</sub>	25 V
V <sub>S</sub> to V <sub>D</sub>	25 V
V <sub>L</sub> to V <sub>-</sub>	30 V
V <sub>IN</sub> to V <sub>-</sub>	30 V
V <sub>L</sub> to V <sub>IN</sub>	6 V
Current (Any Terminal)	30 mA

Storage Temperature	-65 to 150°C
Operating Temperature (A Suffix)	-55 to 125°C
(B Suffix)	-20 to 85°C
Power Dissipation*	
Flat Package**	750 mW
14 Pin DIP***	825 mW

\*All leads soldered or welded to PC board.

\*\*Derate 10 mW/°C above 75°C.

\*\*\*Derate 11 mW/°C above 75°C.

## ELECTRICAL CHARACTERISTICS

All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

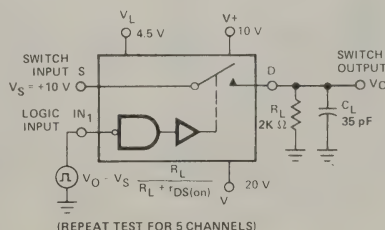
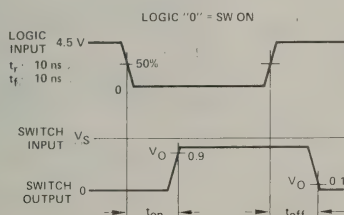
CHARACTERISTIC				MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V <sub>+</sub> = 10 V, V <sub>-</sub> = -20 V, V <sub>L</sub> = 4.5 V		
				A SUFFIX			B SUFFIX						
				-55°C	25°C	125°C	-20°C	25°C	85°C				
1	SWITCH	r <sub>DS(on)</sub>	Drain Source ON Resistance	100	100	125	125	125	150	Ω	V <sub>D</sub> = 10 V	I <sub>S</sub> = -1 mA, V <sub>IN</sub> = 0.5 V	
2			200	200	250	225	225	300	V <sub>D</sub> = 0				
3			450	450	600	500	500	600	V <sub>D</sub> = -10 V				
4	H	I <sub>S(off)</sub>	Source OFF Leakage Current		-1	-1000		-5	-100	nA	V <sub>S</sub> = -10 V, V <sub>D</sub> = 10 V	V <sub>IN</sub> = 4.1 V	
5		I <sub>D(off)</sub>	Drain OFF Leakage Current		-1	-4000		-10	-300		V <sub>D</sub> = -10 V, V <sub>S</sub> = 10 V		
6		I <sub>D(on)</sub> + I <sub>S(on)</sub>	Channel ON Leakage Current		4	4000		10	300		V <sub>D</sub> = 10 V, I <sub>S</sub> = 0		V <sub>IN</sub> = 0.5 V
7	I <sub>N</sub>	I <sub>INL</sub>	Logic Input Current, Input Voltage Low	-0.7	-0.7	-0.7	-1	-1	-1	mA	V <sub>IN</sub> = 0.5 V		
8		I <sub>INH</sub>	Logic Input Current, Input Voltage High	±1	±1	±10	±10	±10	±10		μA	V <sub>IN</sub> = 4.1 V	
9		t <sub>on</sub>	Turn-ON Time		0.3			0.5				μs	See Switching Time Test Circuit
10	t <sub>off</sub>	Turn-OFF Time		2			2						
11	DYNAMIC	C <sub>S(off)</sub>	Source OFF Capacitance		3 Typ*			3 Typ*		pF	V <sub>S</sub> = 0, I <sub>D</sub> = 0		
12		C <sub>D(off)</sub>	Drain OFF Capacitance		7 Typ*			7 Typ*			V <sub>D</sub> = 0, I <sub>S</sub> = 0		
13		Off Isolation			Typ > -50 dB at 5 MHz*						R <sub>L</sub> = 100Ω, C <sub>L</sub> = 3 pF		
14	SUPPLY	I <sub>+</sub>	Positive Supply Current		3			3		mA	V <sub>IN</sub> = 0.5 V, One Channel ON		
15		I <sub>-</sub>	Negative Supply Current		-6			-6					
16		I <sub>L</sub>	Logic Supply Current		3			3					
17		I <sub>+</sub>	Positive Supply Current		15			25		μA	V <sub>IN</sub> = 4.1 V, All Channels OFF		
18		I <sub>-</sub>	Negative Supply Current		-20			-40					
19	I <sub>L</sub>	Logic Supply Current		10			20						

\*Typical Values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

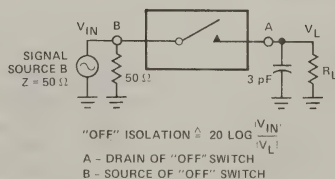
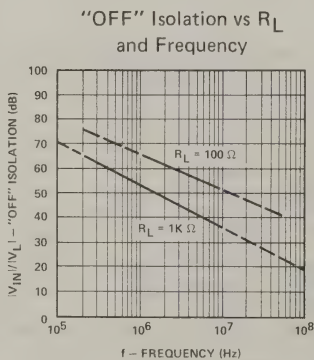
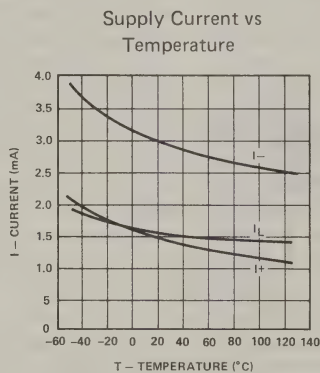
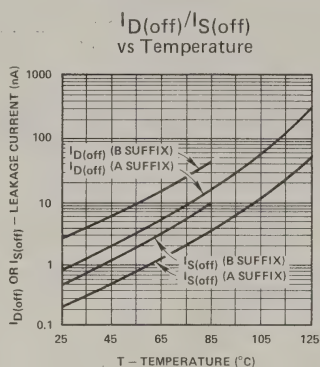
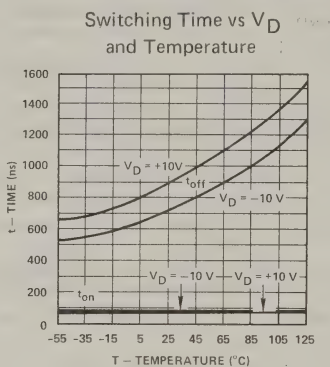
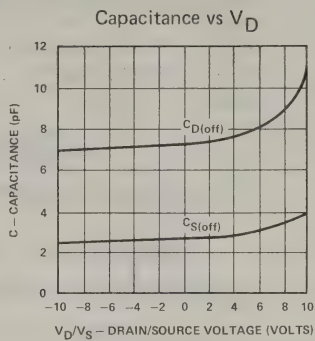
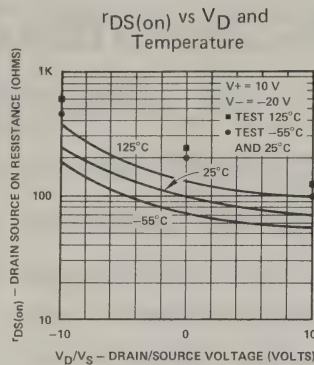
IBAF-B + MABA

## SWITCHING TIME TEST CIRCUIT

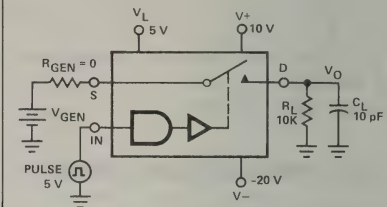
Switch output waveform shown for V<sub>S</sub> = constant with logic input waveform as shown. Note that V<sub>S</sub> may be + or - as per switching time test circuit. V<sub>O</sub> is the steady state output with switch on. Feedthrough via gate capacitance may result in spikes at leading and trailing edge of output waveform.



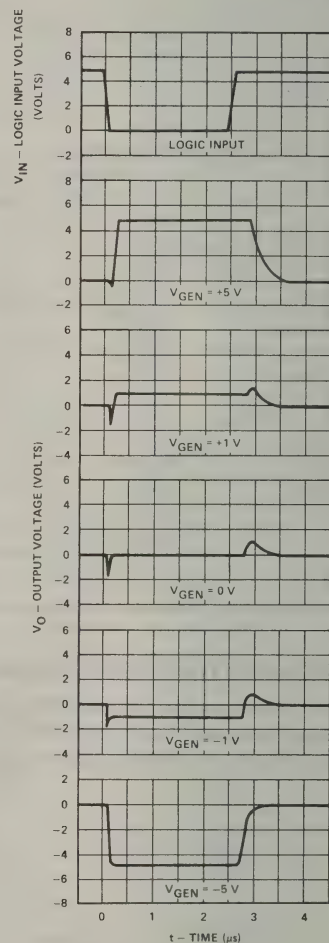
# TYPICAL CHARACTERISTICS



Typical delay, rise, fall, settling times, and switching transients in this circuit.



If  $R_{GEN}$ ,  $R_L$  or  $C_L$  is increased, there will be proportional increases in rise and/or fall RC times.



# 2-Channel Drivers with SPST and DPST FET Switches



designed for . . .

- Switching High Frequencies
- Switching in Satellite Applications
- Portable, Battery Operated Circuits
- Low Signal Distortion Switching Circuits such as Audio Switching

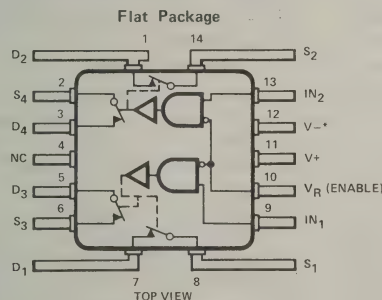
## BENEFITS

- Higher Signal Bandwidth Switching Capabilities
  - OFF Isolation > 60 dB @ 1 MHz
- Better Radiation Resistance than PMOS Drivers
  - Bipolar Drivers
- Minimizes Standby Power Requirements
  - <1 mW Standby Power
- Less Signal Distortion than CMOS or PMOS Switches
  - Constant ON Resistance

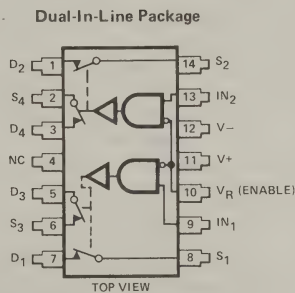
## DESCRIPTION

These switching circuits contain two channels in one package; each channel consists of a driver circuit controlling SPST or DPST junction FET switches. The driver interfaces with DTL, TTL or RTL logic signals for multiplexing, commutating, and D/A converter applications. Logic "1" at the input turns the FET switch ON, and logic "0" turns it OFF. Switches have make-before-break action. It is recommended that the DG185 and DG182 be used for new designs.

## PIN CONFIGURATIONS

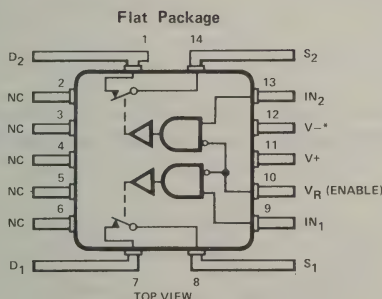


ORDER NUMBER:  
DG126AL  
SEE PACKAGE 5

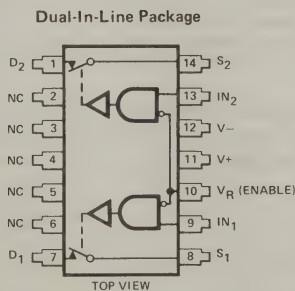


ORDER NUMBERS:  
DG126AP OR DG126BP  
SEE PACKAGE 11

LOGIC	SWITCH
0	OFF
1	ON



ORDER NUMBER:  
DG134AL  
SEE PACKAGE 5

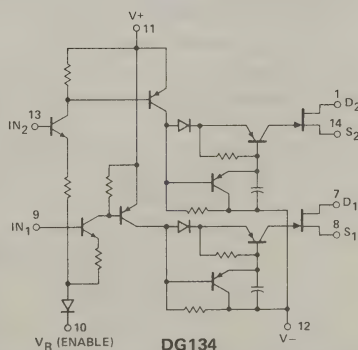
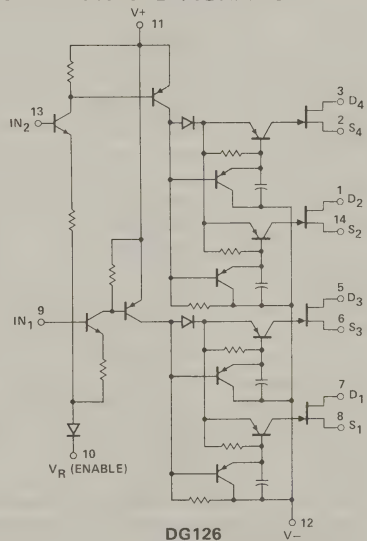


ORDER NUMBERS:  
DG134AP OR DG134BP  
SEE PACKAGE 11

\*Common to Substrate and Base of Package

SWITCH STATES ARE FOR LOGIC "1" INPUT

## SCHEMATIC DIAGRAMS





# ABSOLUTE MAXIMUM RATINGS

V+ to V—	36 V
V+ to VD	36 V
VD or VS to V—	36 V
VD to VS	±22 V
V+ to VR	25 V
VR to V—	25 V
VIN to V—	30 V
V+ to VIN	25 V
VIN to VR	±6 V

Current (Any Terminal)	30 mA
Storage Temperature	–65 to 150°C
Operating Temperature (A Suffix)	–55 to 125°C
(B Suffix)	–20 to 85°C
Power Dissipation*	
Flat Package**	750 mW
14 Pin DIP***	825 mW

\* All leads welded or soldered to PC board.  
 \*\* Derate 10 mW/°C above 75°C.  
 \*\*\* Derate 11 mW/°C above 75°C.

**ELECTRICAL CHARACTERISTICS** All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC			MAX LIMITS							UNIT	TEST CONDITIONS, UNLESS NOTED: V+ = 12 V, V− = −18 V, VR = 0		
			DG126A, DG134A			DG126B, DG134B							
			−55 C	25 C	125 C	−20 C	25 C	85 C					
1	SWITCH	rDS(on)	Drain-Source ON Resistance	80	80	150				Ω	VD = 10 V	IS = −10 mA, VIN = 2.5 V*	
2							100	100	150		VD = 8 V		
3		IS(off)	Source OFF Leakage Current		1	100				nA	VS = 10 V, VD = −10 V	VIN = 0.8 V*	
4								5	100		VS = 8 V, VD = −8 V		
5		ID(off)	Drain OFF Leakage Current		1	100					VD = 10 V, VS = −10 V		
6								5	100		VD = 8 V, VS = −8 V		
7		ID(on) + IS(on)	Channel ON Leakage Current		−2	−100					nA	VD = VS = −10 V	VIN = 2.5 V*
8								−5	−100			VD = VS = −8 V	
9	IIN	Input Current, Input Voltage Low	0.1	0.1	2	4	4	4	μA		VIN = 0.8 V*		
10		Input Current, Input Voltage High	120	60	60	150	100	100			VIN = 2.5 V*		
11	D	ton	Turn-ON Time		0.6			1	μs	See Switching Time Test Circuit			
12		toff	Turn-OFF Time		1.6			2					
13	DYNAMIC	CS(off)	Source OFF Capacitance	2.4 Typical**							pF	VS = 0, ID = 0	f = 1 MHz
14		CD(off)	Drain OFF Capacitance	2.4 Typical**								VD = 0, IS = 0	
15		CD(on) + CS(on)	Channel ON Capacitance	2.8 Typical**								VD = VS = 0	
16		Off Isolation		Typ > 60 dB at 1 MHz**								RL = 75 Ω	
17	SUPPLY	I+	Positive Supply Current		3.0			3.3		mA	VIN = 2.5 V, One Channel ON		
18		I−	Negative Supply Current		−1.8			−2.0					
19		IR	Reference Supply Current		−1.4			−1.5					
20		I+	Positive Supply Current		25			25		μA	Both VIN = 0*, All Channels OFF		
21		I−	Negative Supply Current		−25			−25					
22		IR	Reference Supply Current		−25			−25					

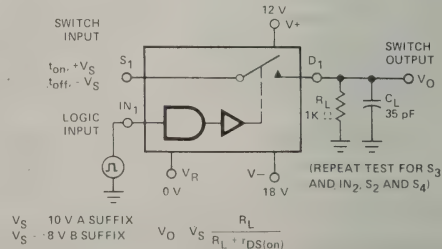
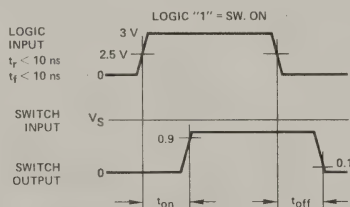
\* VIN must be a step function with a minimum rise and fall rate of 1 V/μs.

LOADC + NC

\*\* Typical Values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

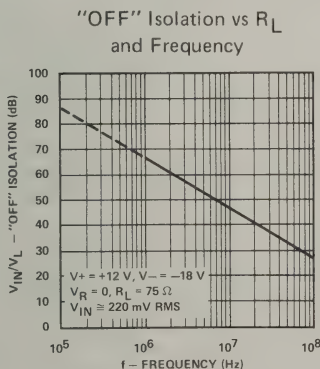
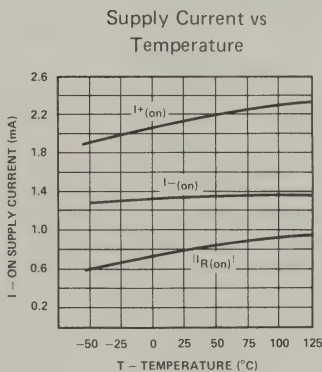
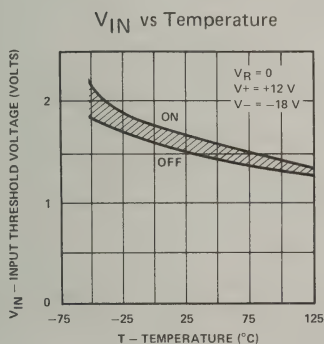
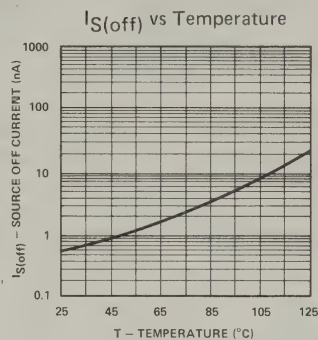
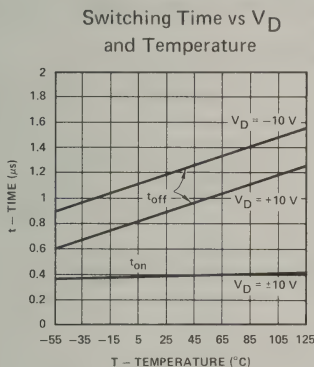
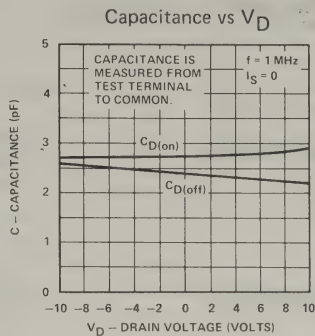
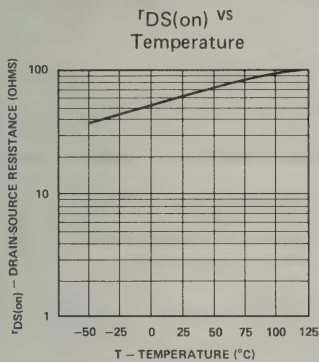
## SWITCHING TIME TEST CIRCUIT

Switch output waveform shown for VS = constant with logic input waveform as shown. Note that VS may be + or – as per switching time test circuit. VO is the steady state output with switch on. Feedthrough via gate capacitance may result in spikes at leading and trailing edge of output waveform.

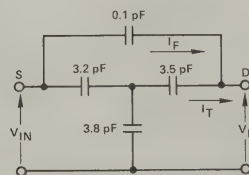




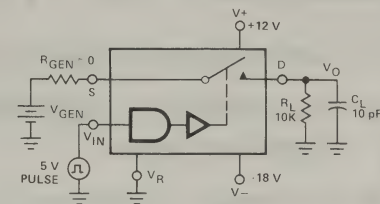
# TYPICAL CHARACTERISTICS



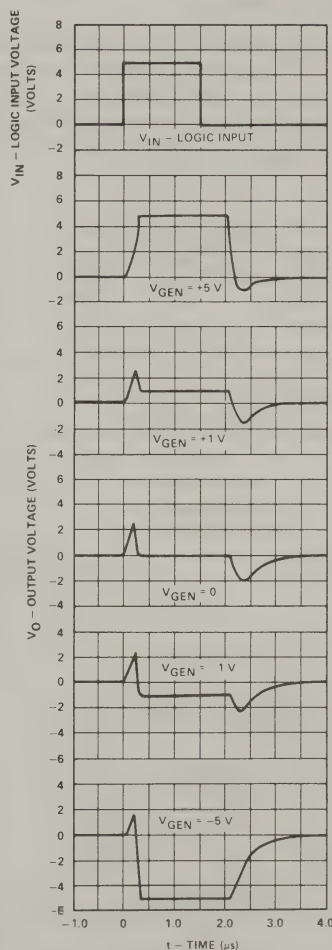
## Equivalent "OFF" Circuit



Typical delay, rise, fall, settling times, and switching transients in this circuit.



If  $R_{GEN}$ ,  $R_L$  or  $C_L$  is increased, there will be proportional increases in rise and/or fall RC times.



DG126 DG134

3

Analog Switches

# 2-Channel Drivers with SPST and DPST FET Switches



*designed for . . .*

- Switching High Frequencies
- Switching in Satellite Applications
- Portable, Battery Operated Circuits
- Low Signal Distortion Switching Circuits such as Audio Switching

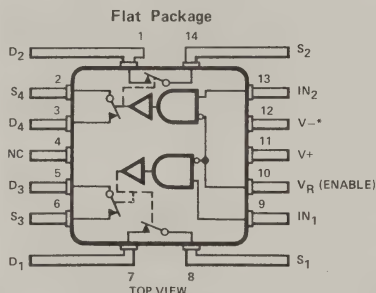
## BENEFITS

- Higher Signal Bandwidth Switching Capabilities
  - OFF Isolation  $> 60 \text{ dB}$  @  $1 \text{ MHz}$
- Better Radiation Resistance than PMOS Drivers
  - Bipolar Drivers
- Minimizes Standby Power Requirements
  - $< 1 \text{ mW}$  Standby Power
- Less Signal Distortion than CMOS or PMOS Switches
  - Constant ON Resistance

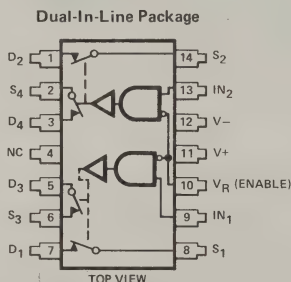
## DESCRIPTION

These switching circuits contain two channels in one package; each channel consists of a driver circuit controlling SPST or DPST junction FET switches. The driver interfaces with DTL, TTL or RTL logic signals for multiplexing, commutating, and D/A converter applications. Logic "1" at the input turns the FET switch ON, and logic "0" turns it OFF. Switches have make-before-break action. It is recommended that the DG184 and DG181 be used for new designs.

## PIN CONFIGURATIONS

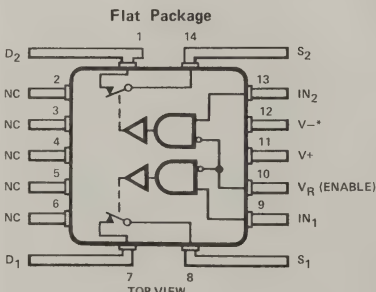


ORDER NUMBER:  
 DG129AL  
 SEE PACKAGE 5

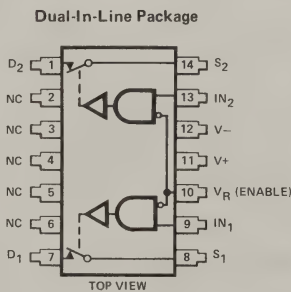


ORDER NUMBERS:  
 DG129AP OR DG129BP  
 SEE PACKAGE 11

LOGIC	SWITCH
0	OFF
1	ON



ORDER NUMBER:  
 DG133AL  
 SEE PACKAGE 5

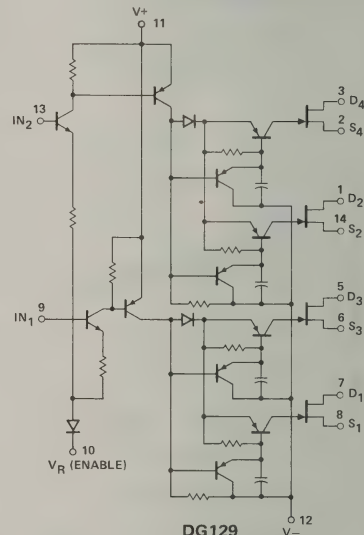


ORDER NUMBERS:  
 DG133AP OR DG133BP  
 SEE PACKAGE 11

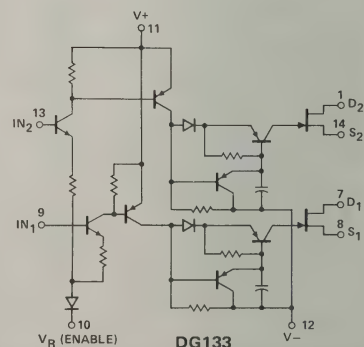
\*Common to Substrate and Base of Package

SWITCH STATES ARE FOR LOGIC "1" INPUT

## SCHEMATIC DIAGRAMS



DG129



DG133

# ABSOLUTE MAXIMUM RATINGS

V+ to V-	36 V
V+ to VD	36 V
VD or VS to V-	36 V
VD to VS	±22 V
V+ to VR	25 V
VR to V-	25 V
VIN to V-	30 V
V+ to VIN	25 V
VIN to VR	±6 V

Current (Any Terminal)	30 mA
Storage Temperature	-65 to 150°C
Operating Temperature (A Suffix)	-55 to 125°C
(B Suffix)	-20 to 85°C

Power Dissipation*	
Flat Package**	750 mW
14 Pin DIP***	825 mW

\*All leads welded or soldered to PC board.

\*\*Derate 10 mW/°C above 75°C.

\*\*\*Derate 11 mW/°C above 75°C.

**ELECTRICAL CHARACTERISTICS** All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC		MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V+ = 12 V, V- = -18 V, VR = 0				
		DG129A, DG133A			DG129B, DG133B								
		-55°C	25°C	125°C	-20°C	25°C	85°C						
1	SWITCH CHARACTERISTICS	rDS(on)	Drain-Source ON Resistance	30	30	60				Ω	VD = 10 V	IS = -10 mA, VIN = 2.5 V*	
2						50	50	75	VD = 8 V				
3		IS(off)	Source OFF Leakage Current		1	100				nA	VS = 10 V, VD = -10 V	VIN = 0.8 V*	
4							5	100	VS = 8 V, VD = -8 V				
5		ID(off)	Drain OFF Leakage Current		1	100					VD = 10 V, VS = -10 V		
6							5	100	VD = 8 V, VS = -8 V				
7		ID(on) + IS(on)	Channel ON Leakage Current		-2	-100					V	VD = VS = -10 V	VIN = 2.5 V*
8							-5	-100	VD = VS = -8 V				
9	IIN	IINL	Input Current, Input Voltage Low	0.1	0.1	2	4	4	4		μA	VIN = 0.8 V*	
10		IINH	Input Current, Input Voltage High	120	60	60	150	100	100			VIN = 2.5 V*	
11	DYNAMIC CHARACTERISTICS	ton	Turn-ON Time		0.6			1		μs	See Switching Time Test Circuit		
12		toff	Turn-OFF Time		1.6			2					
13		CS(off)	Source OFF Capacitance	2.4 Typical**						pF	VS = 0, ID = 0	f = 1 MHz	
14			CD(off)	Drain OFF Capacitance	2.4 Typical**						VD = 0, IS = 0		
15				CD(on) + CS(on)	Channel ON Capacitance	2.8 Typical**							VD = VS = 0
16			Off Isolation		Typ > 60 dB at 1 MHz**								RL = 75 Ω
17		SUPPLY CHARACTERISTICS	I+	Positive Supply Current		3.0			3.3		mA	VIN = 2.5V*, One Channel ON	
18			I-	Negative Supply Current		-1.8			-2.0				
19	IR		Reference Supply Current		-1.4			-1.5					
20	I+		Positive Supply Current		25			25		μA	Both VIN = 0*, All Channels OFF		
21	I-		Negative Supply Current		-25			-25					
22	IR		Reference Supply Current		-25			-25					

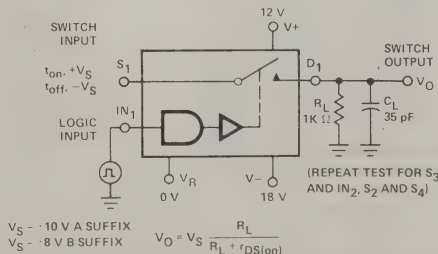
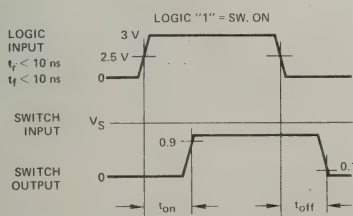
\*VIN must be a step function with a minimum rise and fall rate of 1 V/μs.

LODC + NC

\*\*Typical Values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

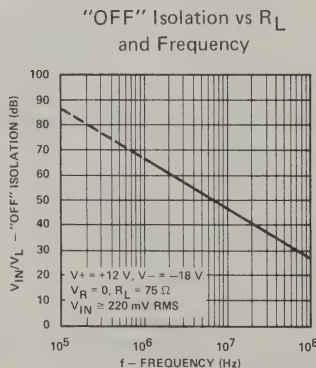
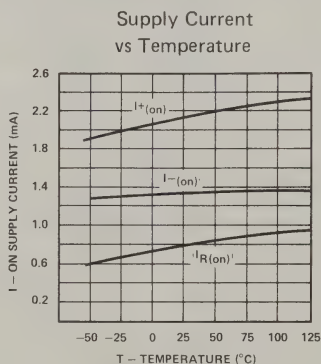
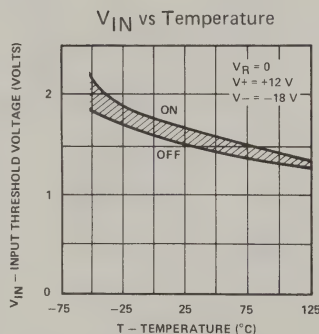
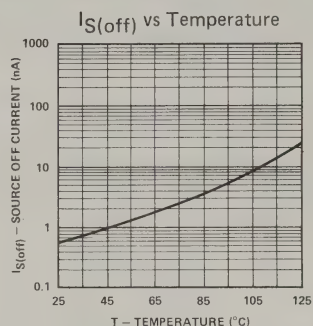
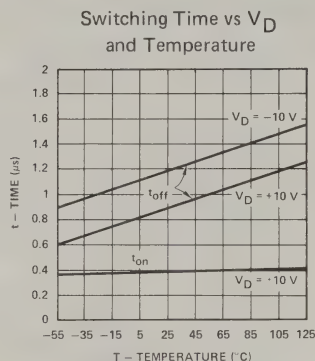
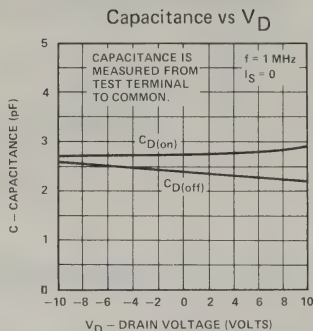
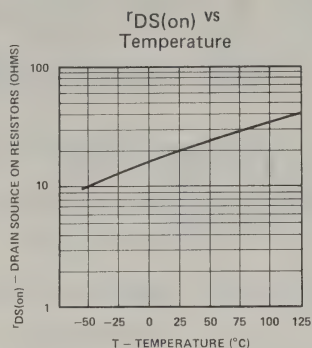
## SWITCHING TIME TEST CIRCUIT

Switch output waveform shown for VS = constant with logic input waveform as shown. Note that VS may be + or - as per switching time test circuit. VO is the steady state output with switch on. Feedthrough via gate capacitance may result in spikes at leading and trailing edge of output waveform.

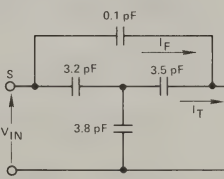




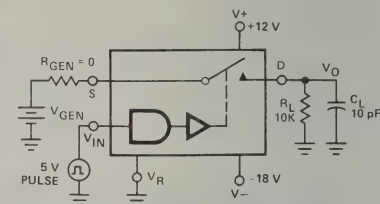
# TYPICAL CHARACTERISTICS



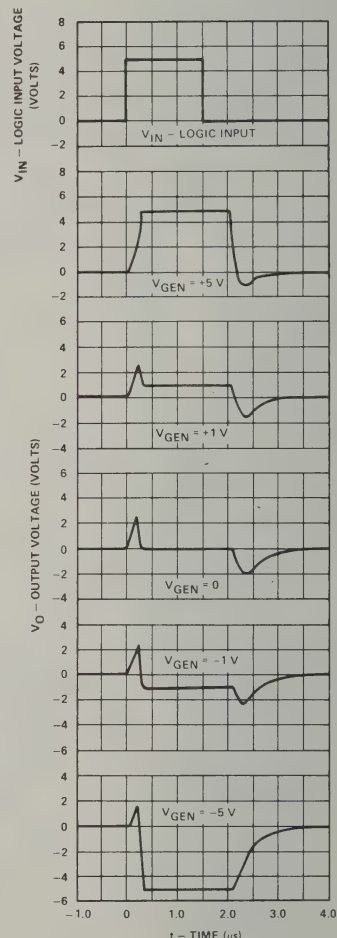
## Equivalent "OFF" Circuit



Typical delay, rise, fall, settling times, and switching transients in this circuit.



If  $R_{GEN}$ ,  $R_L$  or  $C_L$  is increased, there will be proportional increases in rise and/or fall RC times.





# Drivers with Normally Open & Normally Closed FET Switches

**Siliconix**

DG139 DG144

*designed for . . .*

- **Switching High Frequencies**
- **Switching in Satellite Applications**
- **Portable, Battery Operated Circuits**
- **Low Signal Distortion Switching Circuits such as Audio Switching**

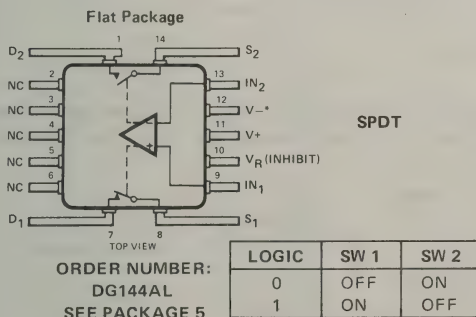
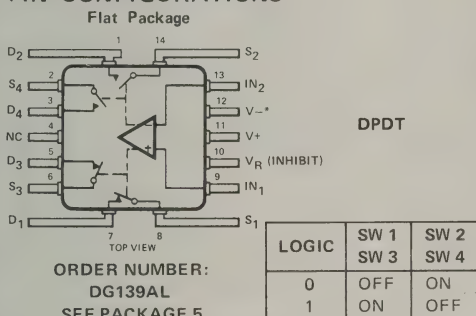
## BENEFITS

- Higher Signal Bandwidth Switching Capabilities
  - OFF Isolation > 60 dB @ 1 MHz
- Better Radiation Resistance than PMOS Drivers
  - Bipolar Drivers
- Minimizes Standby Power Requirements
  - < 1 mW Standby Power
- Less Signal Distortion than CMOS or PMOS Switches
  - Constant ON Resistance

## DESCRIPTION

The DG139 contains four junction-type field-effect transistors designed to function as electronic switches. Level-shifting drivers enable low-level inputs (2 to 3 V) to control the ON-OFF state of the switches. The driver inputs are connected differentially so that with input  $IN_2$  connected to a 2.5 voltage reference, a positive logic "0" at input  $IN_1$  will turn switches 1 and 3 OFF and switches 2 and 4 ON. A positive logic "1" at  $IN_1$  will turn switches 1 and 3 ON and switches 2 and 4 OFF. The normally-grounded  $V_R$  terminal may be used as an "Inhibit" terminal, in which case all switches may be held OFF with a positive voltage applied to  $V_R$ . In the ON state, each switch conducts equally well in either direction, has a series resistance of < 30 ohms, and a shunt leakage of < 2 nA. In the OFF state the switches will hold off voltages up to 20 V peak-to-peak. Switches have make-before-break action. The DG144 is similar to the DG139, except that it contains two FET switches instead of four. It is recommended that the DG190 and DG187 be used for new designs.

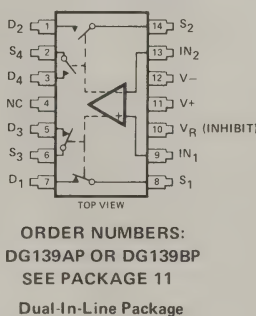
## PIN CONFIGURATIONS



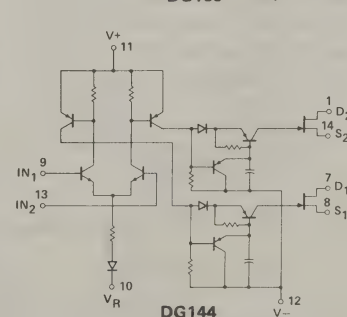
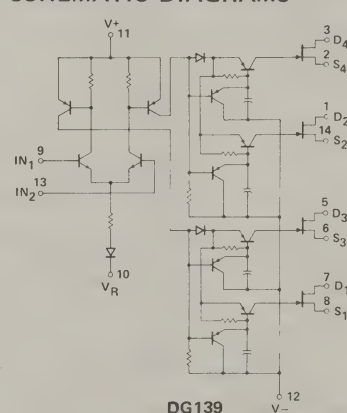
\* Common to Substrate and Base of Package

SWITCH STATES ARE FOR  
 $V_{IN1}$  = LOGIC "1" INPUT AND  $V_{IN2}$  = 2.5 V BIAS  
(POSITIVE LOGIC)

## Dual-In-Line Package



## SCHEMATIC DIAGRAMS



3  
Analog Switches

# ABSOLUTE MAXIMUM RATINGS

V+ to V-, V <sub>D</sub> or V <sub>S</sub> .....	36 V	Storage Temperature .....	-65 to 150°C
V <sub>D</sub> or V <sub>S</sub> to V- .....	36 V	Operating Temperature (A Suffix) .....	-55 to 125°C
V <sub>D</sub> to V <sub>S</sub> .....	±22 V	(B Suffix) .....	-20 to 85°C
V+ to V <sub>R</sub> .....	25 V	Power Dissipation*	
V+ to V <sub>IN1</sub> or V <sub>IN2</sub> .....	25 V	Flat Package** .....	750 mW
V <sub>R</sub> to V- .....	25 V	14 Pin DIP*** .....	825 mW
V <sub>IN1</sub> to V <sub>IN2</sub> .....	±6 V	*All leads welded or soldered to PC board.	
V <sub>IN1</sub> or V <sub>IN2</sub> to V <sub>R</sub> .....	±6 V	**Derate 10 mW/°C above 75°C.	
V <sub>IN1</sub> or V <sub>IN2</sub> to V- .....	30 V	***Derate 11 mW/°C above 75°C.	
Current (Any Terminal) .....	30 mA		

**ELECTRICAL CHARACTERISTICS** All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC			MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V <sub>+</sub> = 12 V, V <sub>-</sub> = -18 V, V <sub>R</sub> = 0, V <sub>IN2</sub> = 2.5 V*		
			A SUFFIX			B SUFFIX						
			-55°C	25°C	125°C	-20°C	25°C	85°C				
1	SWITCHING	r <sub>DS(on)</sub>	Drain-Source ON Resistance	30	30	60			Ω	V <sub>D</sub> = 10 V	I <sub>S</sub> = -10 mA	
2						50	50	75		V <sub>D</sub> = 8 V	V <sub>IN1</sub> = 3 V* (SW <sub>1,3</sub> ON), V <sub>IN1</sub> = 2 V* (SW <sub>2,4</sub> ON)	
3		I <sub>S(off)</sub>	Source OFF Leakage Current		1	100			nA	V <sub>S</sub> = 10 V, V <sub>D</sub> = -10 V	V <sub>IN1</sub> = 2 V* (SW <sub>1,3</sub> OFF) V <sub>IN1</sub> = 3 V* (SW <sub>2,4</sub> OFF)	
4							5	100		V <sub>S</sub> = 8 V, V <sub>D</sub> = -8 V		
5		I <sub>D(off)</sub>	Drain OFF Leakage Current		1	100				V <sub>D</sub> = 10 V, V <sub>S</sub> = -10 V		
6							5	100		V <sub>D</sub> = 8 V, V <sub>S</sub> = -8 V		
7		I <sub>D(on)</sub> + I <sub>S(on)</sub>	Channel ON Leakage Current		-2	-100				V <sub>D</sub> = V <sub>S</sub> = -10 V	V <sub>IN1</sub> = 3 V* (SW <sub>1,3</sub> ON) V <sub>IN1</sub> = 2 V* (SW <sub>2,4</sub> ON)	
8							-5	-100		V <sub>D</sub> = V <sub>S</sub> = -8 V		
9	INPUT	I <sub>IN1L</sub>	Input 1 Current, Input 1 Voltage Low	0.1	0.1	2	4	4	μA	V <sub>IN1</sub> = 2 V*		
10		I <sub>IN2L</sub>	Input 2 Current, Input 2 Voltage Low	0.1	0.1	2	4	4		V <sub>IN2</sub> = 2 V*, V <sub>IN1</sub> = 2.5 V*		
11		I <sub>IN1H</sub>	Input 1 Current, Input 1 Voltage High	120	60	60	150	100		100	V <sub>IN1</sub> = 3 V*	
12		I <sub>IN2H</sub>	Input 2 Current, Input 2 Voltage High	120	60	60	150	100		100	V <sub>IN2</sub> = 3 V*, V <sub>IN1</sub> = 2.5 V*	
13	DYNAMIC	t <sub>on</sub>	Turn-ON Time		0.8			1	μs	See Switching Time Test Circuit		
14		t <sub>off</sub>	Turn-OFF Time		1.6			2				
15		CAPACITANCE	C <sub>S(off)</sub>	Source OFF Capacitance		2.4 Typ			2.4 Typ	pF	V <sub>S</sub> = 0, I <sub>D</sub> = 0	f = 1 MHz
16			C <sub>D(off)</sub>	Drain OFF Capacitance		2.4 Typ			2.4 Typ		V <sub>D</sub> = 0, I <sub>S</sub> = 0	
17	C <sub>D(on)</sub> + C <sub>S(on)</sub>		Channel On Capacitance		2.8 Typ			2.8 Typ	V <sub>D</sub> = V <sub>S</sub> = 0			
18	Off Isolation		Typ > 60 dB at 1 MHz**							R <sub>L</sub> = 75 Ω		
19	SUPPLY	I <sub>+</sub>	Positive Supply Current		4.2			4.5	mA	V <sub>IN1</sub> = 2 V* or V <sub>IN1</sub> = 3 V*, One Channel ON		
20		I <sub>-</sub>	Negative Supply Current		-2			-2.2				
21		I <sub>R</sub>	Reference Supply Current		-2.2			-2.4				
22		I <sub>+</sub>	Positive Supply Current		25			25	μA	V <sub>IN1</sub> = V <sub>IN2</sub> = 0.8 V*, All Channels OFF		
23		I <sub>-</sub>	Negative Supply Current		-25			-25				
24		I <sub>R</sub>	Reference Supply Current		-25			-25				

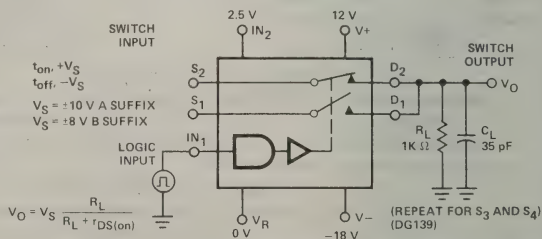
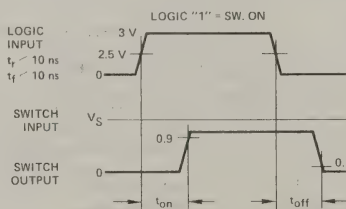
\*V<sub>IN</sub> must be a step function with a minimum rise and fall rate of 1 V/μs.

\*\*Typical values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

LODF + NC

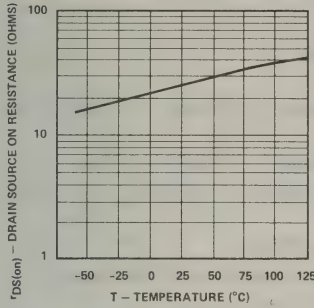
## SWITCHING TIME TEST CIRCUIT

Switch output waveform shown for V<sub>S</sub> = constant with logic input waveform as shown. Note that V<sub>S</sub> may be + or - as per switching time test circuit. V<sub>O</sub> is the steady state output with switch on. Feedthrough via gate capacitance may result in spikes at leading and trailing edge of output waveform.

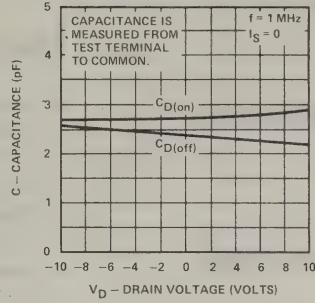


# TYPICAL CHARACTERISTICS

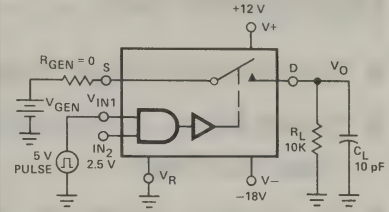
$r_{DS(on)}$  vs Temperature



Capacitance vs  $V_D$

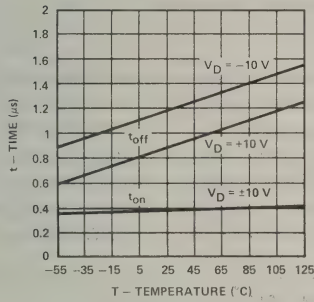


Typical delay, rise, fall, settling times, and switching transients in this circuit.

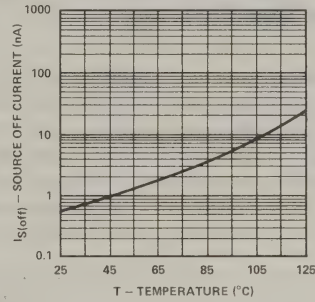


If  $R_{GEN}$ ,  $R_L$  or  $C_L$  is increased, there will be proportional increases in rise and/or fall RC times.

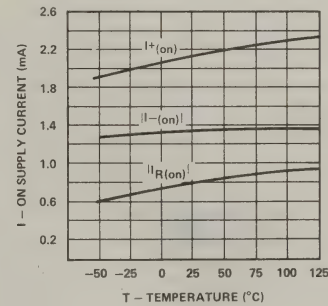
Switching Time vs  $V_D$  and Temperature



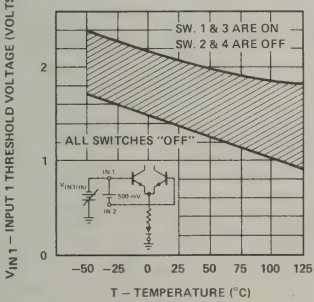
$I_{S(off)}$  vs Temperature



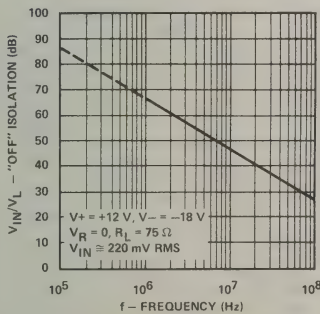
Supply Current vs Temperature



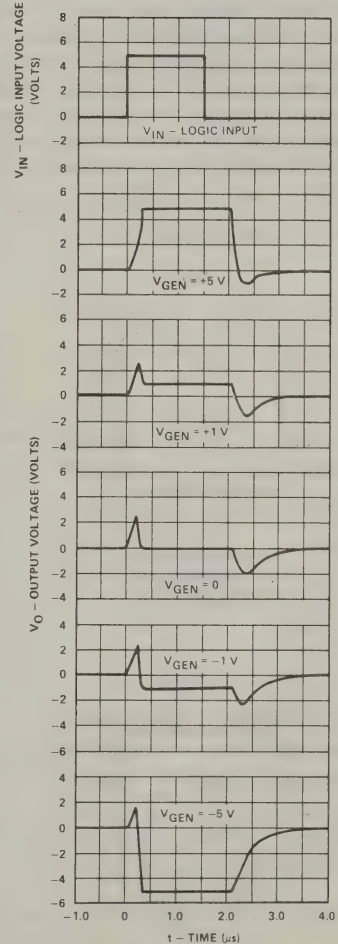
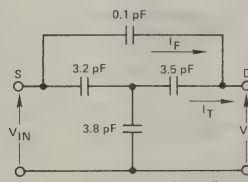
$V_{IN(th)}$  vs Temperature



"OFF" Isolation vs  $R_L$  and Frequency



Equivalent "OFF" Circuit





# 2-Channel Drivers with SPST and DPST FET Switches



*designed for . . .*

- **Switching High Frequencies**
- **Switching in Satellite Applications**
- **Portable, Battery Operated Circuits**
- **Low Signal Distortion Switching Circuits such as Audio Switching**

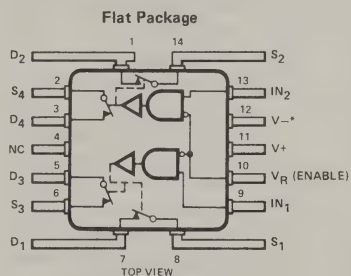
## BENEFITS

- Higher Signal Bandwidth Switching Capabilities
  - OFF Isolation  $> 60$  dB @ 1 MHz
- Better Radiation Resistance than PMOS Drivers
  - Bipolar Drivers
- Minimizes Standby Power Requirements
  - $< 1$  mW Standby Power
- Less Signal Distortion than CMOS or PMOS Switches
  - Constant ON Resistance

## DESCRIPTION

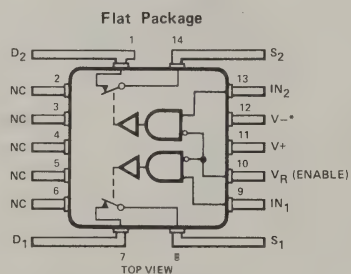
The DG140 contains four junction-type field-effect transistors (JFETs) designed to function as two double-pole single-throw electronic switches. Level-shifting drivers enable low-level inputs (0.8 to 2.5 V) to control the ON-OFF state of each switch. With a positive logic "0" at the driver input the switches will be OFF. With a positive logic "1" at the input the switches will be ON. In the ON state each switch will conduct current in either direction, and in the OFF state each switch will block voltages up to 20 V peak-to-peak. ON series resistance is  $< 10$  ohms, and ON shunt leakage is  $< 2$  nA. With both drivers in the "switch OFF" state total power consumption is  $< 750$   $\mu$ W. Switches have make-before-break action. The DG141 is similar to the DG140 except that it contains two SPST switch functions. It is recommended that the DG183 and DG180 be used for new designs.

## PIN CONFIGURATIONS



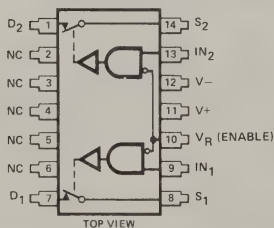
ORDER NUMBER:  
DG140AL  
SEE PACKAGE 5

LOGIC	SWITCH
0	OFF
1	ON



ORDER NUMBER:  
DG141AL  
SEE PACKAGE 5

### Dual-In-Line Package

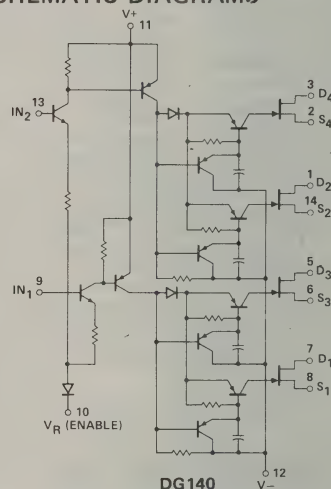


ORDER NUMBERS:  
DG141AP OR DG141BP  
SEE PACKAGE 11

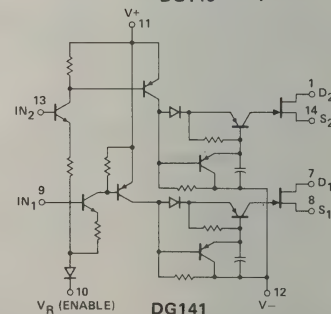
\* Common to Substrate and Base of Package

SWITCH STATES ARE LOGIC "1" INPUT

## SCHEMATIC DIAGRAMS



DG140



DG141



# ABSOLUTE MAXIMUM RATINGS

V+ to V—	36 V
V+ to VD or VS	36 V
VD or VS to V—	32 V
VD to VS	±22 V
V+ to VR	25 V
VR to V—	25 V
VIN to V—	30 V
V+ to VIN	25 V
VIN to VR	±6 V
Current (Any Terminal)	30 mA

Storage Temperature	–65 to 150°C
Operating Temperature (A Suffix)	–55 to 125°C
(B Suffix)	–20 to 85°C
Power Dissipation*	
Flat Package**	750 mW
14 Pin DIP***	825 mW

\*All leads welded or soldered to PC board.

\*\*Derate 10 mW/°C above 75°C.

\*\*\*Derate 11 mW/°C above 75°C.

## ELECTRICAL CHARACTERISTICS

All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC			MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V+ = 12 V, V- = -18 V, VR = 0			
			DG140A, DG141A			DG140B, DG141B							
			-55°C	25°C	125°C	-20°C	25°C	85°C					
1	SWITCH	rDS(on)	Drain-Source ON Resistance	10	10	20				Ω	VD = 10 V	IS = -10 mA, VIN = 2.5 V*	
2							15	15	25		VD = 8 V		
3		IS(off)	Source OFF Leakage Current		10	1000				nA	VS = 10 V, VD = -10 V	VIN = 0.8 V*	
4								15	300		VS = 8 V, VD = -8 V		
5		ID(off)	Drain OFF Leakage Current		10	1000			VD = 10 V, VS = -10 V		VD = 8 V, VS = -8 V		
6								15	300				
7		ID(on) + IS(on)	Channel ON Leakage Current		-2	-100					V	VD = VS = -10 V	VIN = 2.5 V*
8								-5	-100			VD = VS = -8 V	
9	IN	IINL	Input Current, Input Voltage Low	0.1	0.1	2	4	4	4		μA	VIN = 0.8 V*	
10		IINH	Input Current, Input Voltage High	120	60	60	150	100	100			VIN = 2.5 V*	
11	DYNAMIC	ton	Turn-ON Time		1			1.5		μs	See Switching Time Test Circuit		
12		toff	Turn-OFF Time		2.5			2.5					
13		CS(off)	Source OFF Capacitance		** Typ			** Typ		pF	VS = 0, ID = 0	f = 1 MHz	
14				CD(off)	Drain OFF Capacitance		** Typ		** Typ				VD = 0, IS = 0
15						CD(on) + CS(on)	Channel ON Capacitance		2.8 ** Typ				2.8 ** Typ
16		Off Isolation		Typ > 50 dB at 1 MHz**							RL = 100 Ω, CL = 3 pF		
17	SUPPLY	I+	Positive Supply Current		3			3.3		mA	VIN = 2.5 V*, One Channel ON		
18		I-	Negative Supply Current		-1.8			-2					
19		IR	Reference Supply Current		-1.4			-1.5					
20		I+	Positive Supply Current		25			25		μA	Both VIN = 0*, All Channels OFF		
21		I-	Negative Supply Current		-25			-25					
22		IR	Reference Supply Current		-25			-25					

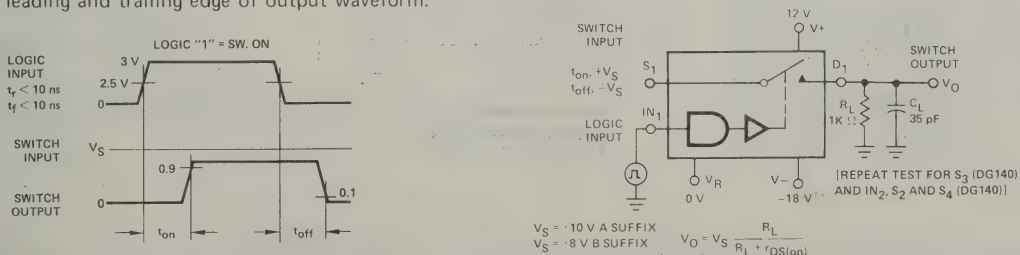
\*VIN must be a step function with a minimum rise and fall rate of 1 V/μs.

\*\*Typical values are for DESIGN AID only, not guaranteed and not subject to production testing.

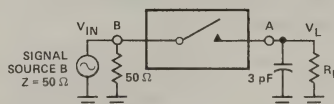
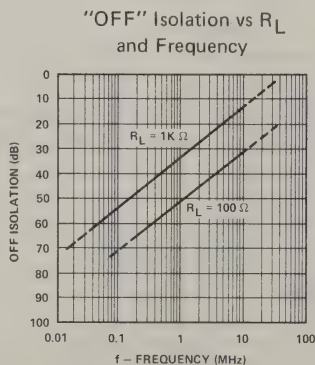
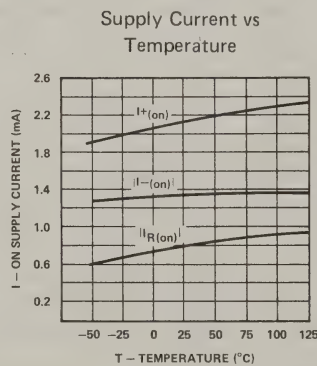
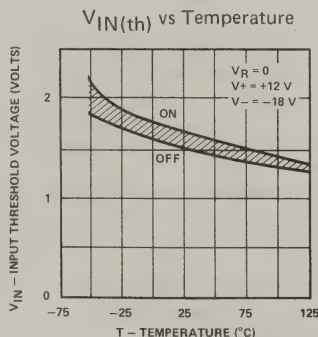
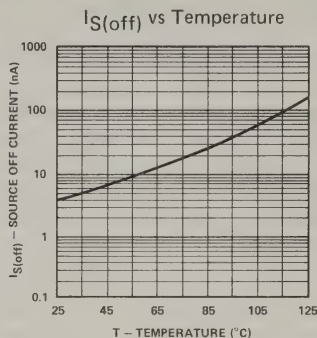
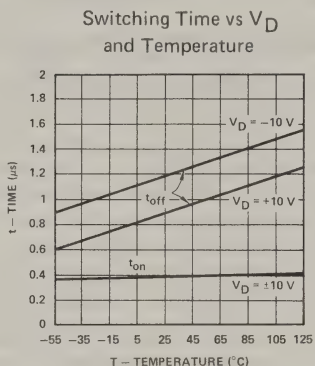
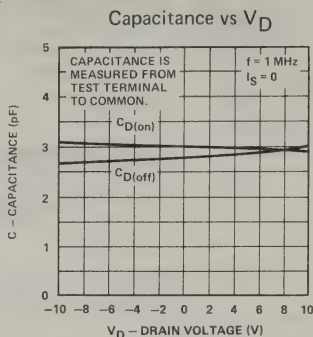
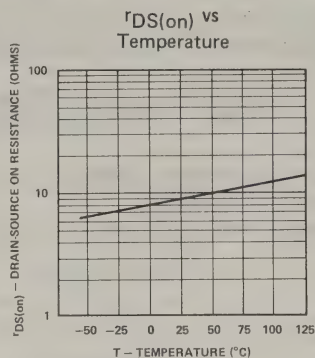
LODC + NIP

## SWITCHING TIME TEST CIRCUIT

Switch output waveform shown for VS = constant with logic input waveform as shown. Note that VS may be + or – as per switching time test circuit. VO is the steady state output with switch on. Feedthrough via gate capacitance may result in spikes at leading and trailing edge of output waveform.



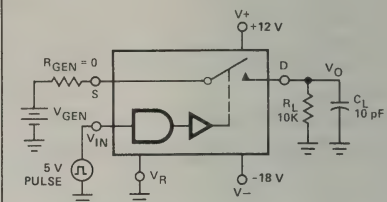
# TYPICAL CHARACTERISTICS



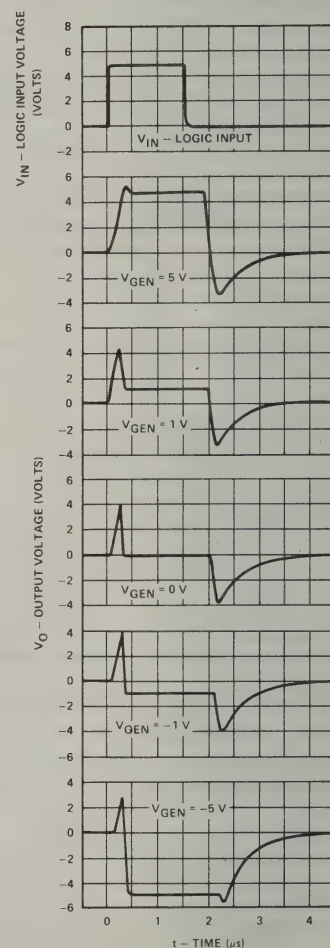
$$\text{"OFF" ISOLATION} \hat{=} 20 \log \frac{|V_{IN}|}{|V_L|}$$

A - DRAIN OF "OFF" SWITCH  
B - SOURCE OF "OFF" SWITCH

Typical delay, rise, fall, settling times, and switching transients in this circuit.



If  $R_{GEN}$ ,  $R_L$  or  $C_L$  is increased, there will be proportional increases in rise and/or fall RC times.



# Drivers with Normally Open & Normally Closed Switches



DG142 DG143

*designed for . . .*

- **Switching High Frequencies**
- **Switching in Satellite Applications**
- **Portable, Battery Operated Circuits**
- **Low Signal Distortion Switching Circuits such as Audio Switching**

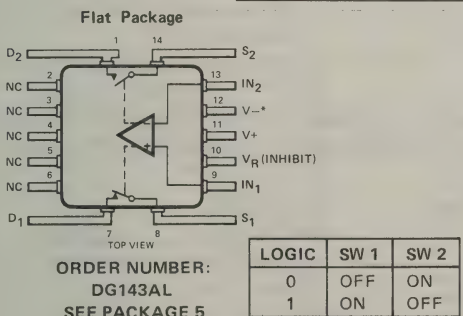
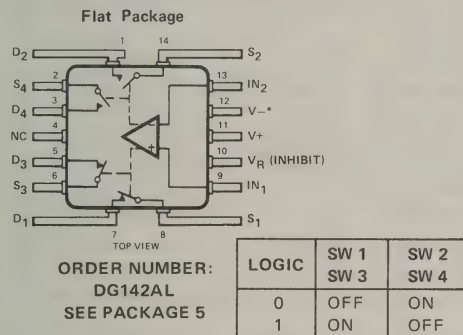
## BENEFITS

- Higher Signal Bandwidth Switching Capabilities
  - OFF Isolation  $> 60$  dB @ 1 MHz
- Better Radiation Resistance than PMOS Drivers
  - Bipolar Drivers
- Minimizes Standby Power Requirements
  - $< 1$  mW Standby Power
- Less Signal Distortion than CMOS or PMOS Switches
  - Constant ON Resistance

## DESCRIPTION

The DG142 contains four junction-type field-effect transistors designed to function as electronic switches. Level-shifting drivers enable low-level inputs (2 to 3 V) to control the ON-OFF state of the switches. The driver inputs are connected differentially so that with input  $IN_2$  connected to a 2.5 voltage reference, a positive logic "0" at input  $IN_1$  will turn switches 1 and 3 OFF and switches 2 and 4 ON. A positive logic "1" at  $IN_1$  will turn switches 1 and 3 ON and switches 2 and 4 OFF. The normally-grounded  $V_R$  terminal may be used as an "Inhibit" terminal, in which case all switches may be held OFF with a positive voltage applied to  $V_R$ . In the ON state, each switch conducts equally well in either direction, has a series resistance of  $< 80$  ohms, and a shunt leakage of  $< 2$  nA. In the OFF state the switches will hold off voltages up to 20 V peak-to-peak. Switches have make-before-break action. The DG143 is similar to the DG142, except that it contains two FET switches instead of four. It is recommended that the DG191 and DG188 be used for new designs.

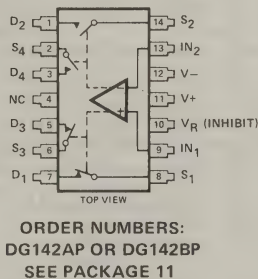
## PIN CONFIGURATIONS



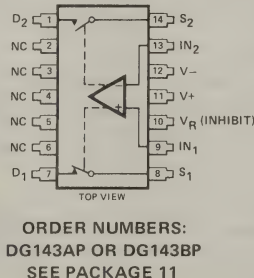
\* Common to Substrate and Base of Package

SWITCH STATES ARE FOR  
 $V_{IN1}$  = LOGIC "1" INPUT AND  $V_{IN2}$  = 2.5 V BIAS  
(POSITIVE LOGIC)

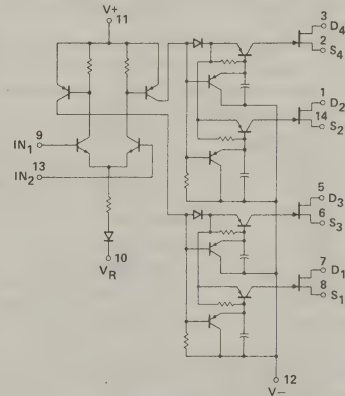
## Dual-In-Line Package



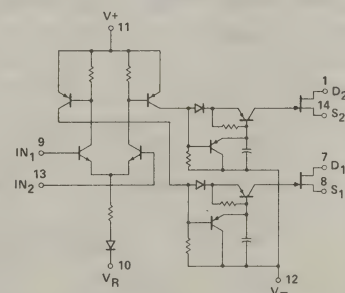
## Dual-In-Line Package



## SCHEMATIC DIAGRAMS



DG142



DG143

3  
Analog Switches



### ABSOLUTE MAXIMUM RATINGS

V+ to V-, VD or VS	36 V
VD or VS to V-	36 V
VD to VS	±22 V
V+ to VR	25 V
V+ to VIN1 or VIN2	25 V
VR to V-	25 V
VIN1 to VIN2	±6 V
VIN1 or VIN2 to VR	±6 V
VIN1 or VIN2 to V-	30 V
Current (Any Terminal)	30 mA

Storage Temperature	.....	-65 to 150°C
Operating Temperature (A Suffix)	.....	-55 to 125°C
(B Suffix)	.....	-20 to 85°C
Power Dissipation*		
Flat Package**	.....	750 mW
14 Pin DIP***	.....	825 mW

\* All leads welded or soldered to PC board.

\*\*Derate 10 mW/°C above 75°C.

\*\*\*Derate 11 mW/°C above 75°C.

**ELECTRICAL CHARACTERISTICS** All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC			MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V <sub>+</sub> = 12 V, V <sub>-</sub> = -18 V, V <sub>R</sub> = 0, V <sub>IN2</sub> = 2.5V*		
			A SUFFIX			B SUFFIX						
			-55 °C	25 °C	125 °C	-20 °C	25 °C	85 °C				
1	SWITCHING	r <sub>DS(on)</sub>	Drain-Source ON Resistance	80	80	150				Ω	V <sub>D</sub> = 10 V	I <sub>S</sub> = -10 mA, V <sub>IN1</sub> = 3 V* (SW <sub>1,3</sub> ON), V <sub>IN1</sub> = 2 V* (SW <sub>2,4</sub> ON)
2						100	100	150	V <sub>D</sub> = 8 V			
3		I <sub>S(off)</sub>	Source OFF Leakage Current		1	100			5	100	V <sub>S</sub> = 10 V, V <sub>D</sub> = -10 V	V <sub>IN1</sub> = 2 V* (SW <sub>1,3</sub> OFF), V <sub>IN1</sub> = 3 V* (SW <sub>2,4</sub> OFF)
4										V <sub>S</sub> = 8 V, V <sub>D</sub> = -8 V		
5		I <sub>D(off)</sub>	Drain OFF Leakage Current		1	100					V <sub>D</sub> = 10 V, V <sub>S</sub> = -10 V	
6								5	100	V <sub>D</sub> = 8 V, V <sub>S</sub> = -8 V		
7		I <sub>D(on)</sub> + I <sub>S(on)</sub>	Channel ON Leakage Current		-2	-100					V <sub>D</sub> = V <sub>S</sub> = -10 V	V <sub>IN1</sub> = 3 V* (SW <sub>1,3</sub> ON), V <sub>IN1</sub> = 2 V* (SW <sub>2,4</sub> ON)
8								-5	-100	V <sub>D</sub> = V <sub>S</sub> = -8 V		
9	INPUT	I <sub>IN1L</sub>	Input 1 Current, Input 1 Voltage Low	0.1	0.1	2	4	4	4	μA	V <sub>IN1</sub> = 2 V*	
10		I <sub>IN2L</sub>	Input 2 Current, Input 2 Voltage Low	0.1	0.1	2	4	4	4		V <sub>IN2</sub> = 2 V*, V <sub>IN1</sub> = 2.5 V*	
11		I <sub>IN1H</sub>	Input 1 Current, Input 1 Voltage High	120	60	60	150	100	100		V <sub>IN1</sub> = 3 V*	
12		I <sub>IN2H</sub>	Input 2 Current, Input 2 Voltage High	120	60	60	150	100	100		V <sub>IN2</sub> = 3 V*, V <sub>IN1</sub> = 2.5 V*	
13	DYNAMIC	t <sub>on</sub>	Turn-ON Time		0.8			1		μs	See Switching Time Test Circuit	
14		t <sub>off</sub>	Turn-OFF Time		1.6			2				
15		C <sub>S(off)</sub>	Source OFF Capacitance		2.4 Typ			2.4 Typ				
16	C <sub>D(off)</sub>	Drain OFF Capacitance		2.4 Typ			2.4 Typ		V <sub>D</sub> = 0, I <sub>S</sub> = 0			
17	C <sub>D(on)</sub> + C <sub>S(on)</sub>	Channel ON Capacitance		2.8 Typ			2.8 Typ		V <sub>D</sub> = V <sub>S</sub> = 0			
18	Off Isolation			Typ > 60 dB at 1 MHz**							R <sub>L</sub> = 75 Ω	
19	SUPPLY	I <sub>+</sub>	Positive Supply Current		4.2			4.5		mA	V <sub>IN1</sub> = 2 V* or V <sub>IN1</sub> = 3 V*, One Channel ON	
20		I <sub>-</sub>	Negative Supply Current		-2			-2.2				
21		I <sub>R</sub>	Reference Supply Current		-2.2			-2.4				
22		I <sub>+</sub>	Positive Supply Current		25			25		μA	V <sub>IN1</sub> = V <sub>IN2</sub> = 0.8 V*, All Channels OFF	
23		I <sub>-</sub>	Negative Supply Current		-25			-25				
24		I <sub>R</sub>	Reference Supply Current		-25			-25				

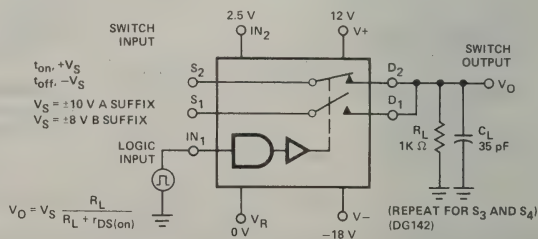
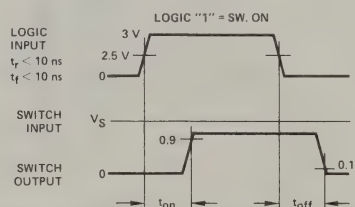
\* $V_{IN}$  must be a step function with a minimum rise and fall rate of 1 V/ $\mu$ s.

**\*\*Typical values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.**

LODF + NC

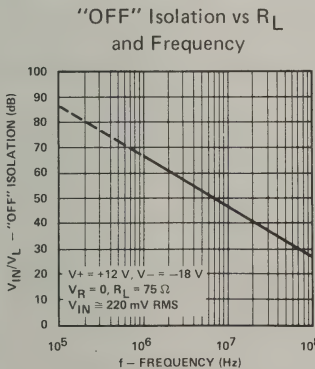
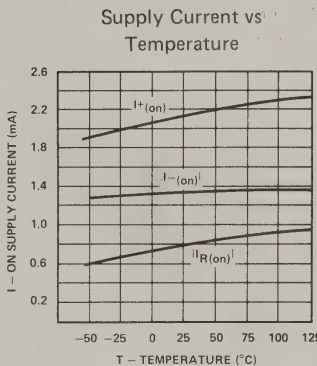
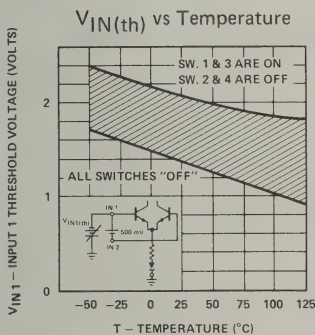
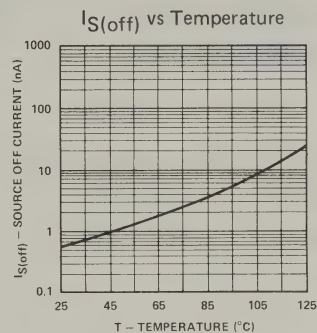
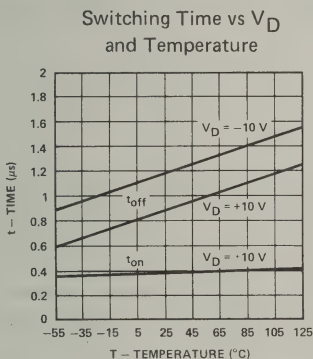
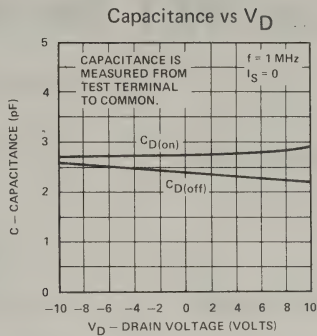
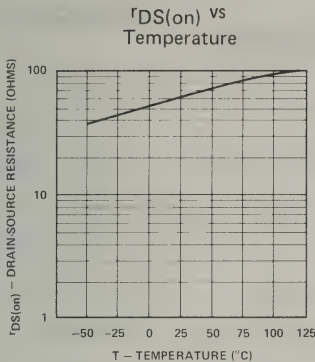
### SWITCHING TIME TEST CIRCUIT

Switch output waveform shown for  $V_S = \text{constant}$  with logic input waveform as shown. Note that  $V_S$  may be + or – as per switching time test circuit.  $V_O$  is the steady state output with switch on. Feedthrough via gate capacitance may result in spikes at leading and trailing edge of output waveform.

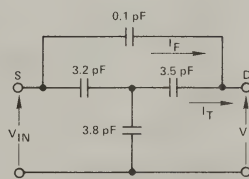




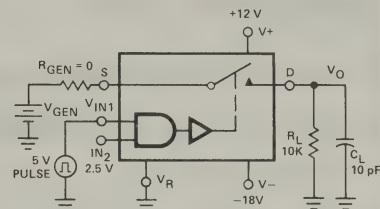
# TYPICAL CHARACTERISTICS



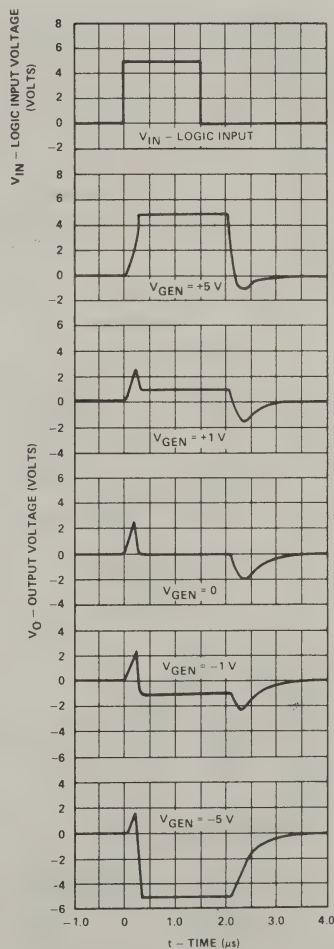
## Equivalent "OFF" Circuit



Typical delay, rise, fall, settling times, and switching transients in this circuit.



If  $R_{GEN}$ ,  $R_L$  or  $C_L$  is increased, there will be proportional increases in rise and/or fall RC times.



# Drivers with Normally Open & Normally Closed FET Switches



*designed for . . .*

- **Switching High Frequencies**
- **Switching in Satellite Applications**
- **Portable, Battery Operated Circuits**
- **Low Signal Distortion Switching Circuits such as Audio Switching**

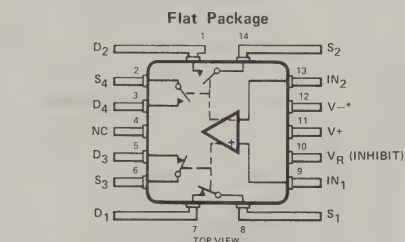
## BENEFITS

- Higher Signal Bandwidth Switching Capabilities
  - OFF Isolation > 60 dB @ 1 MHz
- Better Radiation Resistance than PMOS Drivers
  - Bipolar Drivers
- Minimizes Standby Power Requirements
  - <1 mW Standby Power
- Less Signal Distortion than CMOS or PMOS Switches
  - Constant ON Resistance

## DESCRIPTION

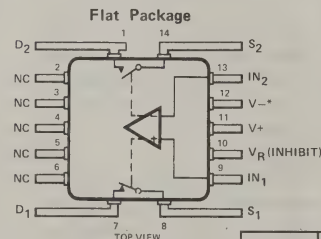
The DG145 contains four junction-type field-effect transistors designed to function as electronic switches. Level-shifting drivers enable low-level inputs (2 to 3 V) to control the ON-OFF state of the switches. The driver inputs are connected differentially so that with input IN<sub>2</sub> connected to a 2.5 voltage reference, a positive logic "0" at input IN<sub>1</sub> will turn switches 1 and 3 OFF and switches 2 and 4 ON. A positive logic "1" at IN<sub>1</sub> will turn switches 1 and 3 ON and switches 2 and 4 OFF. The normally-grounded V<sub>R</sub> terminal may be used as an "Inhibit" terminal, in which case all switches may be held OFF with a positive voltage applied to V<sub>R</sub>. In the ON state, each switch conducts equally well in either direction, has a series resistance of < 10 ohms, and a shunt leakage of < 2 nA. In the OFF state the switches will hold off voltages up to 20 V peak-to-peak. Switches have make-before-break action. The DG146 is similar to the DG145 except that it contains two FET switches instead of four. It is recommended that the DG189 and DG186 be used for new designs.

## PIN CONFIGURATIONS



ORDER NUMBER:  
DG145AL  
SEE PACKAGE 5

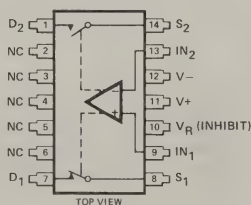
LOGIC	SW 1 SW 3	SW 2 SW 4
0	OFF	ON
1	ON	OFF



ORDER NUMBER:  
DG146AL  
SEE PACKAGE 5

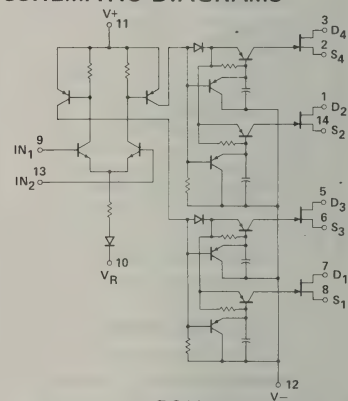
LOGIC	SW 1	SW 2
0	OFF	ON
1	ON	OFF

## Dual-In-Line Package

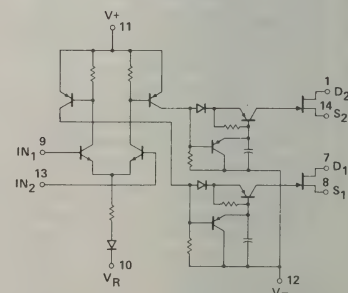


ORDER NUMBERS:  
DG146AP OR DG146BP  
SEE PACKAGE 11

## SCHEMATIC DIAGRAMS



DG145



DG146

\* Common to Substrate and Base of Package

SWITCH STATES ARE FOR  
V<sub>IN1</sub> = LOGIC "1" INPUT AND V<sub>IN2</sub> = 2.5 V BIAS  
(POSITIVE LOGIC)

# ABSOLUTE MAXIMUM RATINGS

V <sub>+</sub> to V <sub>-</sub> , V <sub>D</sub> or V <sub>S</sub> . . . . .	36 V
V <sub>D</sub> or V <sub>S</sub> to V <sub>-</sub> . . . . .	32 V
V <sub>D</sub> to V <sub>S</sub> . . . . .	±22 V
V <sub>+</sub> to V <sub>R</sub> . . . . .	25 V
V <sub>+</sub> to V <sub>IN1</sub> or V <sub>IN2</sub> . . . . .	25 V
V <sub>R</sub> to V <sub>-</sub> . . . . .	25 V
V <sub>IN1</sub> to V <sub>IN2</sub> . . . . .	±6 V
V <sub>IN1</sub> or V <sub>IN2</sub> to V <sub>R</sub> . . . . .	±6 V
V <sub>IN1</sub> or V <sub>IN2</sub> to V <sub>-</sub> . . . . .	30 V

Current (Any Terminal). . . . .	30 mA
Storage Temperature . . . . .	-65 to 150°C
Operating Temperature (A Suffix). . . . .	-55 to 125°C
(B Suffix). . . . .	-20 to 85°C

## Power Dissipation\*

Flat Package** . . . . .	750 mW
14 Pin DIP*** . . . . .	825 mW

\*All leads welded or soldered to PC board.

\*\*Derate 10 mW/°C above 75°C.

\*\*\*Derate 11 mW/°C above 75°C.

**ELECTRICAL CHARACTERISTICS** All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC			MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V <sub>+</sub> = 12 V, V <sub>-</sub> = -18 V, V <sub>R</sub> = 0, V <sub>IN2</sub> = 2.5 V*				
			A SUFFIX			B SUFFIX								
			-55°C	25°C	125°C	-20°C	25°C	85°C						
1	SWITCHING	r <sub>DS(on)</sub>	Drain-Source ON Resistance	10	10	20			Ω	V <sub>D</sub> = 10 V	I <sub>S</sub> = -10 mA V <sub>IN1</sub> = 3 V* (SW <sub>1,3</sub> ON), V <sub>IN1</sub> = 2 V* (SW <sub>2,4</sub> ON)			
2							15	15		25		V <sub>D</sub> = 8 V		
3		I <sub>D</sub>	I <sub>S(off)</sub>	Source OFF Leakage Current		10	1000			nA	V <sub>S</sub> = 10 V, V <sub>D</sub> = -10 V	V <sub>IN1</sub> = 2 V* (SW <sub>1,3</sub> OFF), V <sub>IN1</sub> = 3 V* (SW <sub>2,4</sub> OFF)		
4									15		300		V <sub>S</sub> = 8 V, V <sub>D</sub> = -8 V	
5			I <sub>D(off)</sub>	Drain OFF Leakage Current		10	1000				V <sub>D</sub> = 10 V, V <sub>S</sub> = -10 V			
6								15	300		V <sub>D</sub> = 8 V, V <sub>S</sub> = -8 V			
7			I <sub>D(on)</sub> + I <sub>S(on)</sub>	Channel ON Leakage Current		-2	-100				V <sub>D</sub> = V <sub>S</sub> = -10 V		V <sub>IN1</sub> = 3 V* (SW <sub>1,3</sub> ON), V <sub>IN1</sub> = 2 V* (SW <sub>2,4</sub> ON)	
8									-5		-100			V <sub>D</sub> + V <sub>S</sub> = -8 V
9	I <sub>N</sub>	I <sub>IN1L</sub>	Input 1 Current, Input 1 Voltage Low	0.1	0.1	2	4	4	4	μA	V <sub>IN1</sub> = 2 V*			
10		I <sub>IN2L</sub>	Input 2 Current, Input 2 Voltage Low	0.1	0.1	2	4	4	4		V <sub>IN2</sub> = 2 V*, V <sub>IN1</sub> = 2.5 V*			
11		I <sub>IN1H</sub>	Input 1 Current, Input 1 Voltage High	120	60	60	150	100	100		V <sub>IN1</sub> = 3 V*			
12		I <sub>IN2H</sub>	Input 2 Current, Input 2 Voltage High	120	60	60	150	100	100		V <sub>IN2</sub> = 3 V*, V <sub>IN1</sub> = 2.5 V*			
13	DYNAMIC	t <sub>on</sub>	Turn-ON Time		1			1.5		μs	See Switching Time Test Circuit			
14		t <sub>off</sub>	Turn-OFF Time		2.5			2.5						
15		C <sub>S(off)</sub>	Source OFF Capacitance		3** Typ			3** Typ				pF	V <sub>S</sub> = 0, I <sub>D</sub> = 0	f = 1 MHz
16		C <sub>D(off)</sub>	Drain OFF Capacitance		3** Typ			3** Typ					V <sub>D</sub> = 0, I <sub>S</sub> = 0	
17	C <sub>D(on)</sub> + C <sub>S(on)</sub>	Channel ON Capacitance		2.8** Typ			2.8** Typ		V <sub>D</sub> + V <sub>S</sub> = 0					
18	Off Isolation		Typ > 50 dB at f = 1 MHz**						R <sub>L</sub> = 100 Ω, C <sub>L</sub> = 3 pF					
19	SUPPLY	I <sub>+</sub>	Positive Supply Current		4.2			4.5		mA	V <sub>IN1</sub> = 2 V* or V <sub>IN1</sub> = 3 V*, One Channel ON			
20		I <sub>-</sub>	Negative Supply Current		-2			-2.2						
21		I <sub>R</sub>	Reference Supply Current		-2.2			-2.4						
22		I <sub>+</sub>	Positive Supply Current		25			25		μA	V <sub>IN1</sub> = V <sub>IN2</sub> = 0.8 V*, All Channels OFF			
23		I <sub>-</sub>	Negative Supply Current		-25			-25						
24		I <sub>R</sub>	Reference Supply Current		-25			-25						

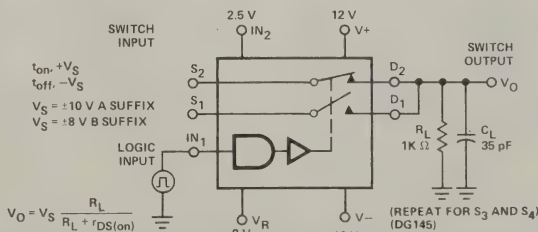
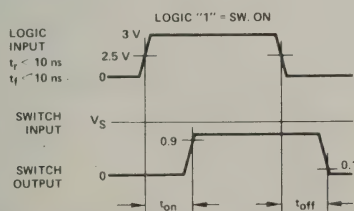
\*V<sub>IN</sub> must be a step function with a minimum rise and fall rate of 1 V/μs.

\*\*Typical values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

LODF + NIP

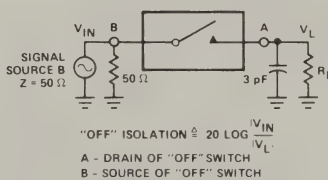
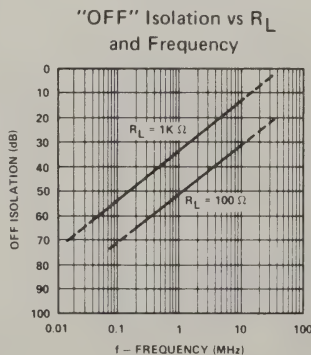
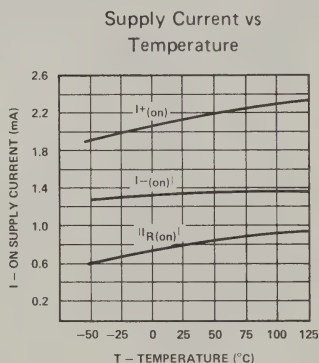
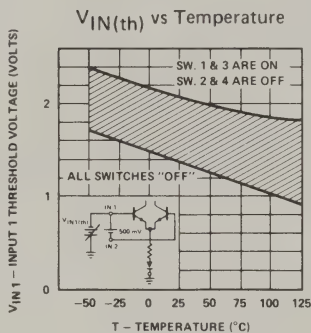
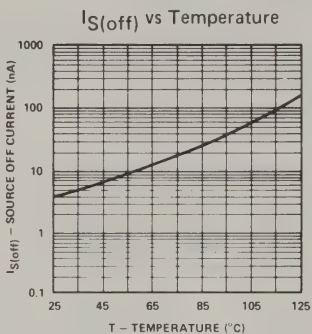
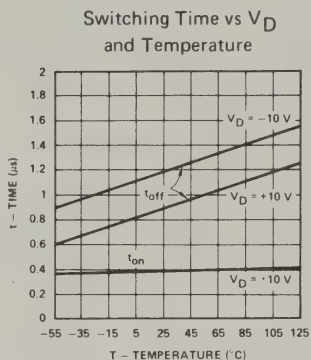
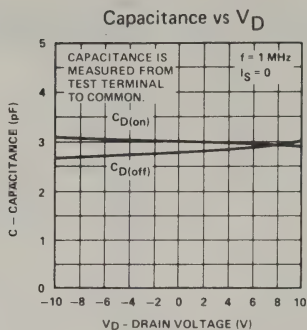
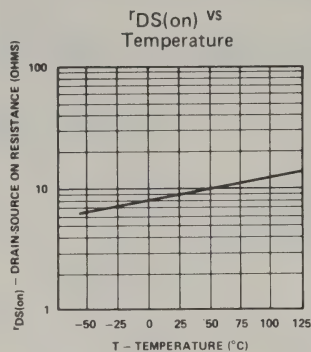
## SWITCHING TIME TEST CIRCUIT

Switch output waveform shown for V<sub>S</sub> = constant with logic input waveform as shown. Note that V<sub>S</sub> may be + or - as per switching time test circuit. V<sub>O</sub> is the steady state output with switch on. Feedthrough via gate capacitance may result in spikes at leading and trailing edge of output waveform.

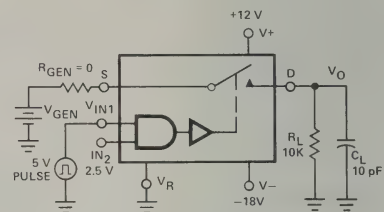




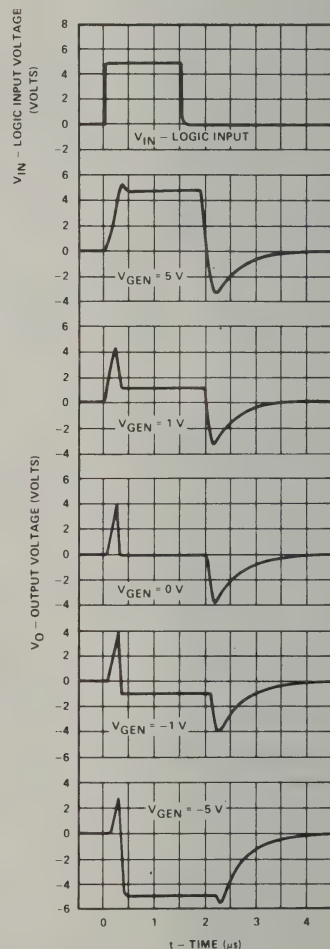
# TYPICAL CHARACTERISTICS



Typical delay, rise, fall, settling times, and switching transients in this circuit.



If  $R_{GEN}$ ,  $R_L$  or  $C_L$  is increased, there will be proportional increases in rise and/or fall RC times.





# 2-Channel Drivers with SPST and DPST FET Switches

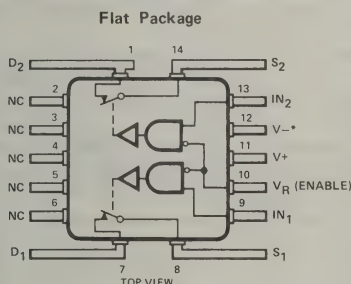
designed for . . .

- Switching High Frequencies
- Switching in Satellite Applications
- Portable, Battery Operated Circuits
- Low Signal Distortion Switching Circuits such as Audio Switching

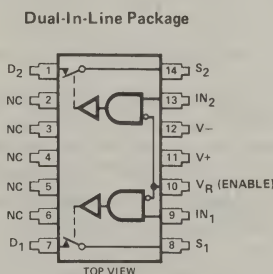
## DESCRIPTION

The DG153 contains four junction-type field-effect transistors (JFETs) designed to function as two double-pole single-throw electronic switches. Level-shifting drivers enable low-level inputs (0.8 to 2.5 V) to control the ON-OFF state of each switch. With a positive logic "0" at the driver input the switches will be OFF. With a positive logic "1" at the input the switches will be ON. In the ON state each switch will conduct current in either direction, and in the OFF state each switch will block voltages up to 15 V peak-to-peak. ON series resistance is  $< 15$  ohms, and ON shunt leakage is  $< 2$  nA. With both drivers in the "switch OFF" state total power consumption is  $< 750$   $\mu$ W. Switches have make-before-break action. The DG151 is similar to the DG153 except that it contains two SPST switch functions. It is recommended that the DG180 and DG183 be used for new designs.

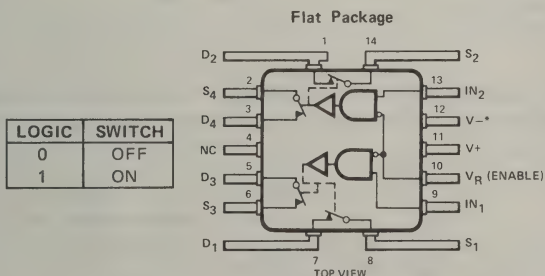
## PIN CONFIGURATIONS



ORDER NUMBER:  
DG151AL  
SEE PACKAGE 5



ORDER NUMBERS:  
DG151AP OR DG151BP  
SEE PACKAGE 11



ORDER NUMBER:  
DG153AL  
SEE PACKAGE 5

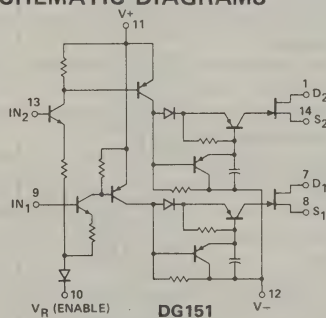
\*Common to Substrate and Base of Package  
SWITCH STATES ARE FOR LOGIC "1" INPUT

LOGIC	SWITCH
0	OFF
1	ON

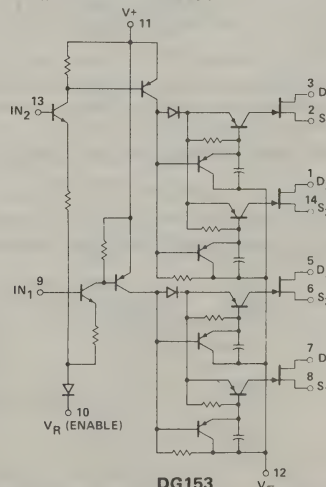
## BENEFITS

- Higher Signal Bandwidth Switching Capabilities
  - OFF Isolation  $> 60$  dB @ 1 MHz
- Better Radiation Resistance than PMOS Drivers
  - Bipolar Drivers
- Minimizes Standby Power Requirements
  - $< 1$  mW Standby Power
- Less Signal Distortion than CMOS or PMOS Switches
  - Constant ON Resistance

## SCHEMATIC DIAGRAMS



DG151



DG153

DG151 DG153

3  
Analog Switches

# ABSOLUTE MAXIMUM RATINGS

V+ to V- or V <sub>D</sub>	36 V
V <sub>D</sub> to V-	32 V
V <sub>D</sub> to V <sub>S</sub>	±22 V
V+ to V <sub>R</sub>	25 V
V+ to V <sub>IN1</sub> or V <sub>IN2</sub>	25 V
V <sub>R</sub> to V-	25 V
V <sub>IN1</sub> to V <sub>IN2</sub>	±6 V
V <sub>IN1</sub> or V <sub>IN2</sub> to V <sub>R</sub>	±6 V
V <sub>IN1</sub> or V <sub>IN2</sub> to V-	30 V

Current (Any Terminal)	30 mA
Storage Temperature	-65 to 150°C
Operating Temperature (A Suffix)	-55 to 125°C
(B Suffix)	-20 to 85°C

## Power Dissipation\*

Flat Package**	750 mW
14 Pin DIP***	825 mW

\*All leads welded or soldered to PC board.

\*\*Derate 10 mW/°C above 75°C.

\*\*\*Derate 11 mW/°C above 75°C.

# ELECTRICAL CHARACTERISTICS

All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC			MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V+ = 15 V, V- = -15 V, V <sub>R</sub> = 0		
			DG151A, DG153A			DG151B, DG153B						
			-55° C	25° C	125° C	-20° C	25° C	85° C				
1	SWITCHING	r <sub>DS(on)</sub>	Drain-Source ON Resistance	15	15	30				Ω	V <sub>D</sub> = 7.5 V	I <sub>S</sub> = -10 mA, V <sub>IN</sub> = 2.5 V*
2						20	20	35		V <sub>D</sub> = 5.5 V		
3		I <sub>S(off)</sub>	Source OFF Leakage Current		10	1000					V <sub>S</sub> = 7.5 V, V <sub>D</sub> = -7.5 V	V <sub>IN</sub> = 0.8 V*
4							15	300			V <sub>S</sub> = 5.5 V, V <sub>D</sub> = -5.5 V	
5		I <sub>D(off)</sub>	Drain OFF Leakage Current		10	1000					V <sub>D</sub> = 7.5 V, V <sub>S</sub> = -7.5 V	
6							15	300			V <sub>D</sub> = 5.5 V, V <sub>S</sub> = -5.5 V	
7		I <sub>D(on)</sub> + I <sub>S(on)</sub>	Channel ON Leakage Current		-2	-100					V <sub>D</sub> = V <sub>S</sub> = -7.5 V	V <sub>IN</sub> = 2.5 V*
8							-5	-100			V <sub>D</sub> = V <sub>S</sub> = -5.5 V	
9	I <sub>N</sub>	I <sub>INL</sub>	Input Current, Input Voltage Low	0.1	0.1	2	4	4	4	μA	V <sub>IN</sub> = 0.8 V*	
10		I <sub>INH</sub>	Input Current, Input Voltage High	120	60	60	150	100	100		V <sub>IN</sub> = 2.5 V*	
11	DYNAMIC	t <sub>on</sub>	Turn-ON Time		1			1.5		μs	See Switching Time Test Circuit	
12		t <sub>off</sub>	Turn-OFF Time		2.5			2.5				
13		C <sub>S(off)</sub>	Source OFF Capacitance		3** Typ			3** Typ				
14	C <sub>D(off)</sub>	Drain OFF Capacitance		3** Typ			3** Typ			V <sub>D</sub> = 0, I <sub>S</sub> = 0		
15	C <sub>D(on)</sub> + C <sub>S(on)</sub>	Channel ON Capacitance		2.8** Typ			2.8** Typ			V <sub>D</sub> = V <sub>S</sub> = 0		
16	Off Isolation			Typ > 50 dB at 1 MHz**							R <sub>L</sub> = 100 Ω, C <sub>L</sub> = 3 pF	
17	SUPPLY	I+	Positive Supply Current		3			3.3		mA	V <sub>IN</sub> = 2.5 V*, One Channel ON	
18		I-	Negative Supply Current		-1.8			-2				
19		I <sub>R</sub>	Reference Supply Current		-1.4			-1.5				
20		I+	Positive Supply Current		25			25		μA	V <sub>IN</sub> = 0*, All Channels OFF	
21		I-	Negative Supply Current		-25			-25				
22		I <sub>R</sub>	Reference Supply Current		-25			-25				

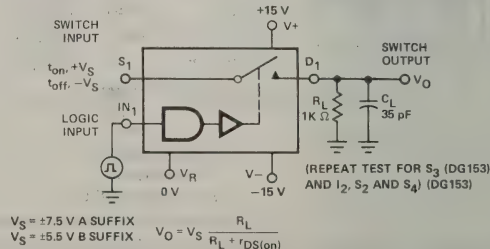
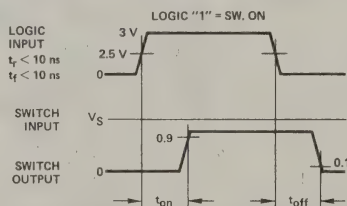
\*V<sub>IN</sub> must be a step function with a minimum rise and fall rate of 1 V/μs.

\*\*Typical values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

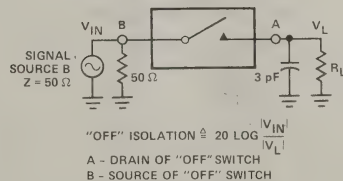
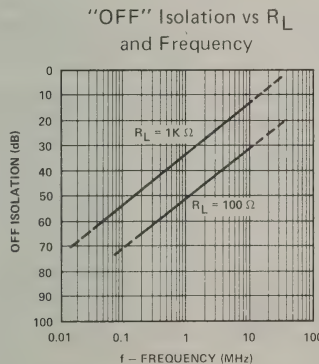
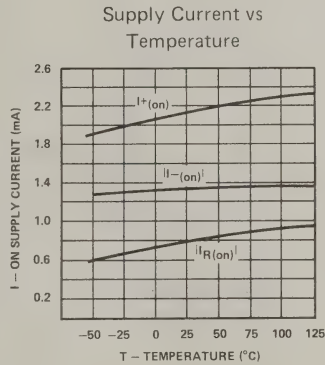
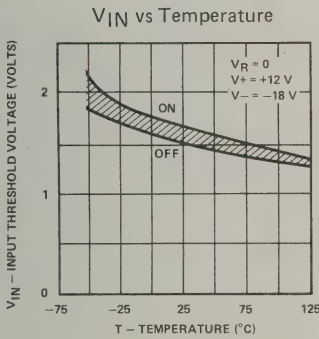
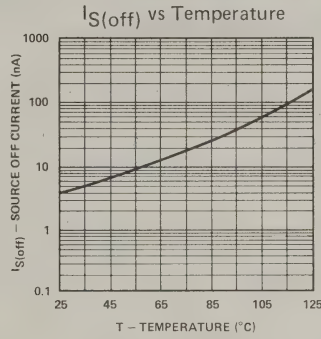
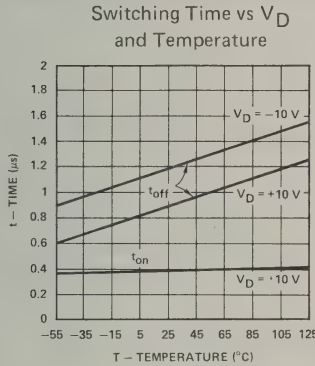
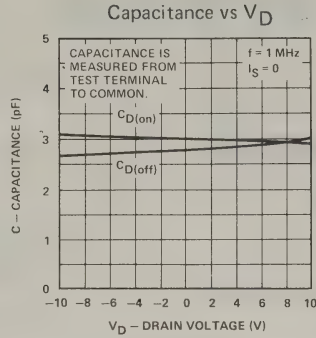
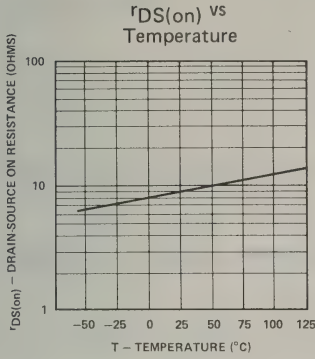
LODC + NIP

# SWITCHING TIME TEST CIRCUIT

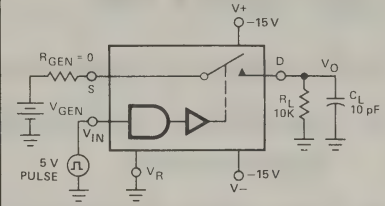
Switch output waveform shown for V<sub>S</sub> = constant with logic input waveform as shown. Note that V<sub>S</sub> may be + or - as per switching time test circuit. V<sub>O</sub> is the steady state output with switch on. Feedthrough via gate capacitance may result in spikes at leading and trailing edge of output waveform.



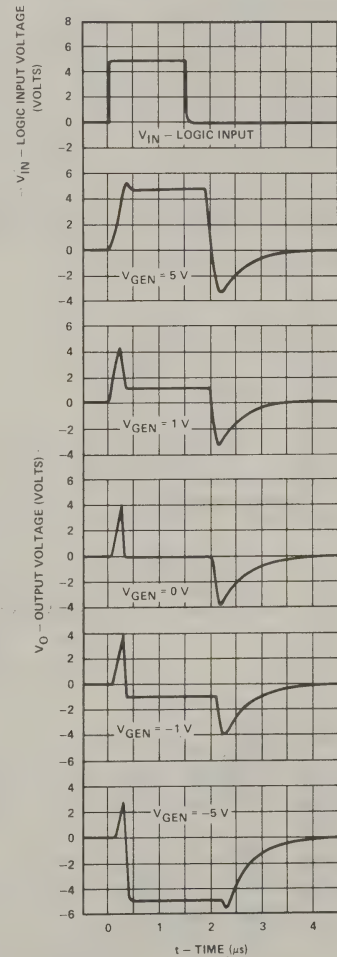
# TYPICAL CHARACTERISTICS



Typical delay, rise, fall, settling times, and switching transients in this circuit.



If  $R_{GEN}$ ,  $R_L$  or  $C_L$  is increased, there will be proportional increases in rise and/or fall RC times.





# 2-Channel Drivers with SPST and DPST FET Switches



*designed for . . .*

- **Switching High Frequencies**
- **Switching in Satellite Applications**
- **Portable, Battery Operated Circuits**
- **Low Signal Distortion Switching Circuits such as Audio Switching**

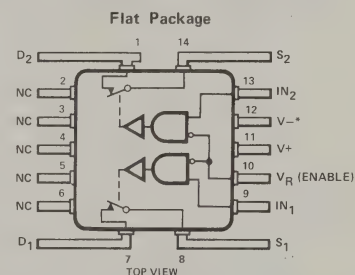
## BENEFITS

- Higher Signal Bandwidth Switching Capabilities
  - OFF Isolation > 60 dB @ 1 MHz
- Better Radiation Resistance than PMOS Drivers
  - Bipolar Drivers
- Minimizes Standby Power Requirements
  - < 1 mW Standby Power
- Less Signal Distortion than CMOS or PMOS Switches
  - Constant ON Resistance

## DESCRIPTION

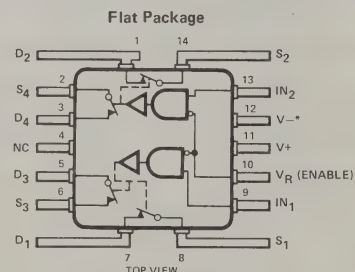
The DG154 contains four junction-type field-effect transistors (JFETs) designed to function as two double-pole single-throw electronic switches. Level-shifting drivers enable low-level inputs (0.8 to 2.5 V) to control the ON-OFF state of each switch. With a positive logic "0" at the driver input the switches will be OFF. With a positive logic "1" at the input the switches will be ON. In the ON state each switch will conduct current in either direction, and in the OFF state each switch will block voltages up to 15 V peak-to-peak. ON series resistance is < 50 ohms, and ON shunt leakage is < 2 nA. With both drivers in the "switch OFF" state total power consumption is < 750  $\mu$ W. Switches have make-before-break action. The DG152 is similar to the DG154 except that it contains two SPST switch functions. It is recommended that the DG181 (or DG182) and DG184 (or DG185) be used for new designs.

## PIN CONFIGURATIONS



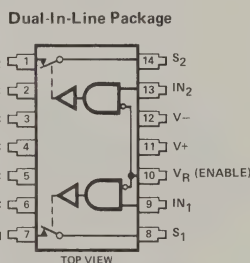
ORDER NUMBER:  
DG152AL  
SEE PACKAGE 5

LOGIC	SWITCH
0	OFF
1	ON

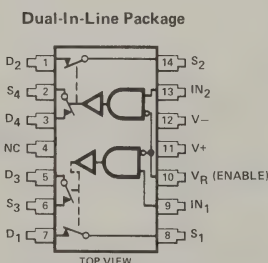


ORDER NUMBER:  
DG154AL  
SEE PACKAGE 5

\* Common to Substrate and Base of Package



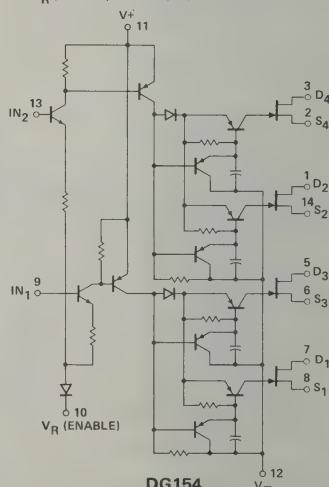
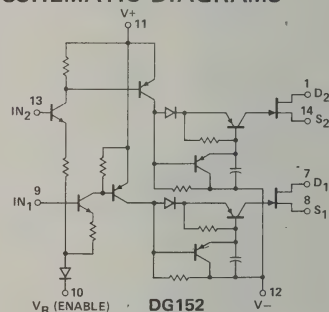
ORDER NUMBERS:  
DG152AP OR DG152BP  
SEE PACKAGE 11



ORDER NUMBERS:  
DG154AP OR DG154BP  
SEE PACKAGE 11

SWITCH STATES ARE FOR LOGIC "1" INPUT

## SCHEMATIC DIAGRAMS





# ABSOLUTE MAXIMUM RATINGS

V <sub>+</sub> to V <sub>-</sub> or V <sub>D</sub>	36 V
V <sub>D</sub> to V <sub>-</sub>	36 V
V <sub>D</sub> to V <sub>S</sub>	±22 V
V <sub>+</sub> to V <sub>R</sub>	25 V
V <sub>+</sub> to V <sub>IN1</sub> or V <sub>IN2</sub>	25 V
V <sub>R</sub> to V <sub>-</sub>	25 V
V <sub>IN1</sub> to V <sub>IN2</sub>	±6 V
V <sub>IN1</sub> or V <sub>IN2</sub> to V <sub>R</sub>	±6 V
V <sub>IN1</sub> or V <sub>IN2</sub> to V <sub>-</sub>	30 V

Current (Any Terminal)	30 mA
Storage Temperature	-65 to 150°C
Operating Temperature (A Suffix)	-55 to 125°C
(B Suffix)	-20 to 85°C

Power Dissipation*	
Flat Package**	750 mW
14 Pin DIP***	825 mW

\*All leads welded or soldered to PC board.

\*\*Derate 10 mW/°C above 75°C.

\*\*\*Derate 11 mW/°C above 75°C.

# ELECTRICAL CHARACTERISTICS

All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC			MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V <sub>+</sub> = 15 V, V <sub>-</sub> = -15 V, V <sub>R</sub> = 0		
			DG152A, DG154A			DG152B, DG154B						
			-55°C	25°C	125°C	-20°C	25°C	85°C				
1	r <sub>DS(on)</sub>	Drain-Source ON Resistance	50	50	100				Ω	V <sub>D</sub> = 7.5 V	I <sub>S</sub> = -10 mA V <sub>IN</sub> = 2.5 V *	
2						100	150	V <sub>D</sub> = 5.5 V				
3	S W I T C H	Source OFF Leakage Current		1	100				nA	V <sub>S</sub> = 7.5 V, V <sub>D</sub> = -7.5 V	V <sub>IN</sub> = 0.8 V *	
4						5	100	V <sub>S</sub> = 5.5 V, V <sub>D</sub> = -5.5 V				
5		Drain OFF Leakage Current		1	100			V <sub>D</sub> = 7.5 V, V <sub>S</sub> = -7.5 V				
6						5	100	V <sub>D</sub> = 5.5 V, V <sub>S</sub> = -5.5 V				
7		Channel ON Leakage Current		-2	-100			V <sub>D</sub> = V <sub>S</sub> = -7.5 V		V <sub>IN</sub> = 2.5 V *		
8						-5	-100	V <sub>D</sub> = V <sub>S</sub> = -5.5 V				
9	I <sub>IN</sub>	Input Current, Input Voltage Low	0.1	0.1	2	4	4	4	μA	V <sub>IN</sub> = 0.8 V *		
10		Input Current, Input Voltage High	120	60	60	150	100	100		V <sub>IN</sub> = 2.5 V *		
11	t <sub>on</sub>	Turn-ON Time		0.6			1		μs	See Switching Time Test Circuit		
12	t <sub>off</sub>	Turn-OFF Time		1.6			2					
13	D Y N A M I C	Source OFF Capacitance		2.4 Typ			2.4 Typ		pF	V <sub>S</sub> = 0, I <sub>D</sub> = 0	f = 1 MHz	
14		Drain OFF Capacitance		2.4 Typ			2.4 Typ			V <sub>D</sub> = 0, I <sub>S</sub> = 0		
15		Channel ON Capacitance		2.8 Typ			2.8 Typ			V <sub>D</sub> = V <sub>S</sub> = 0		
16		Off Isolation		Typ > 60 dB at 1 MHz **								R <sub>L</sub> = 75 Ω
17	S U P P L Y	Positive Supply Current		3			3.3		mA	V <sub>IN</sub> = 2.5 V *, One Channel ON		
18		Negative Supply Current		-1.8			-2					
19		Reference Supply Current		-1.4			-1.5					
20		I <sub>+</sub>	Positive Supply Current		25			25		μA	V <sub>IN</sub> = 0 *, All Channels OFF	
21		I <sub>-</sub>	Negative Supply Current		-25			-25				
22		I <sub>R</sub>	Reference Supply Current		-25			-25				

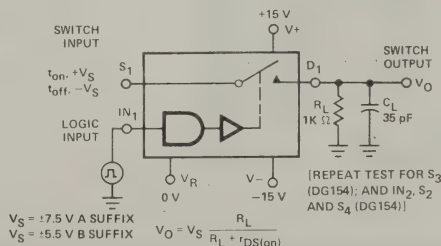
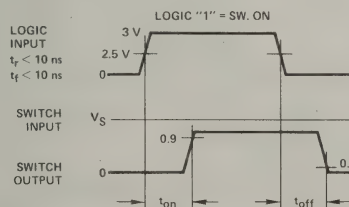
\*V<sub>IN</sub> must be a step function with a minimum rise and fall rate of 1 V/μs.

\*\*Typical values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

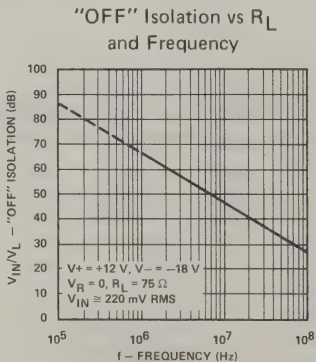
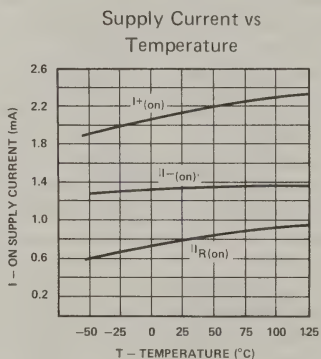
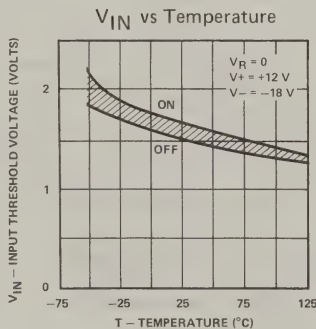
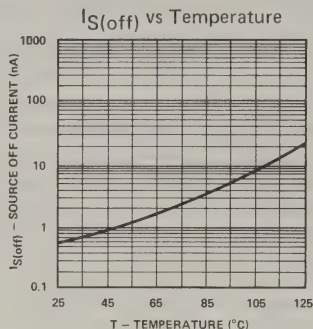
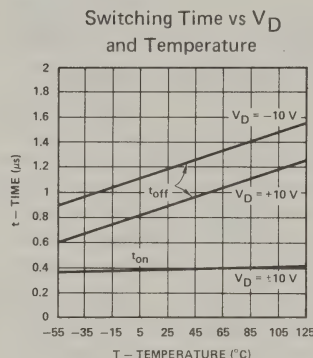
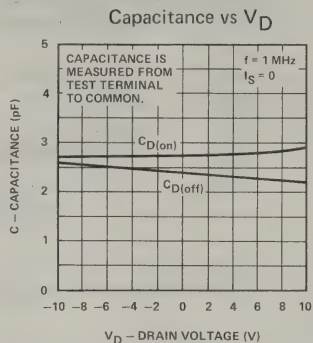
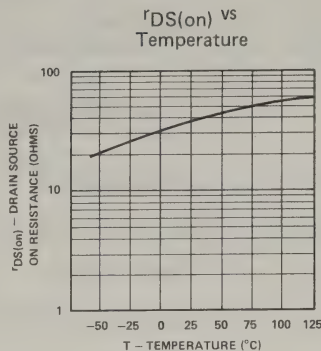
LODC + NC

# SWITCHING TIME TEST CIRCUIT

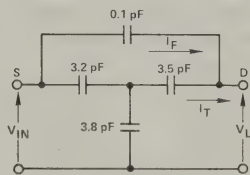
Switch output waveform shown for V<sub>S</sub> = constant with logic input waveform as shown. Note that V<sub>S</sub> may be + or - as per switching time test circuit. V<sub>O</sub> is the steady state output with switch on. Feedthrough via gate capacitance may result in spikes at leading and trailing edge of output waveform.



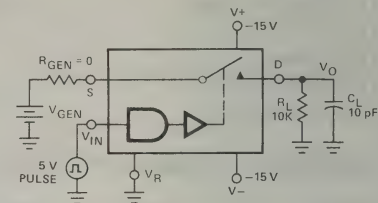
# TYPICAL CHARACTERISTICS



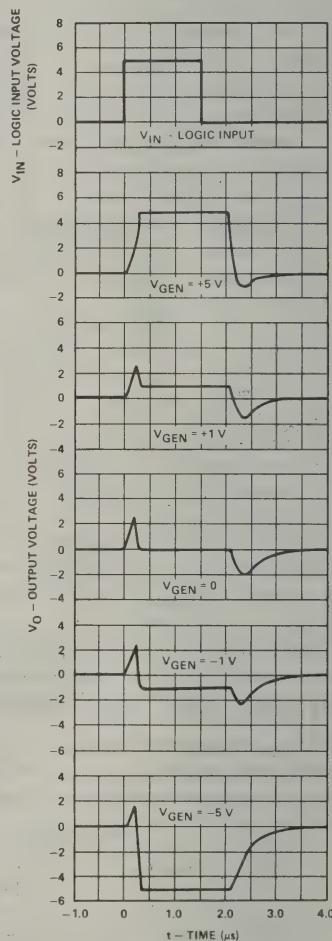
## Equivalent "OFF" Circuit



Typical delay, rise, fall, setting times, and switching transients in this circuit.



If  $R_{GEN}$ ,  $R_L$  or  $C_L$  is increased, there will be proportional increases in rise and/or fall RC times.



# Drivers with Differentially Driven Normally Open and Normally Closed FET Switches designed for . . .

- **Switching High Frequencies**
- **Switching in Satellite Applications**
- **Portable, Battery Operated Circuits**
- **Low Signal Distortion Switching Circuits such as Audio Switching**

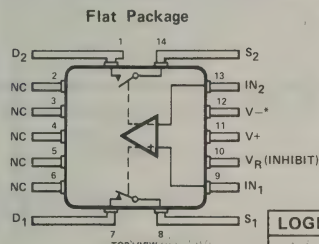
## BENEFITS

- Higher Signal Bandwidth Switching Capabilities
  - OFF Isolation > 60 dB @ 1 MHz
- Better Radiation Resistance than PMOS Drivers
  - Bipolar Drivers
- Minimizes Standby Power Requirements
  - < 1 mW Standby Power
- Less Signal Distortion than CMOS or PMOS Switches
  - Constant ON Resistance

## DESCRIPTION

The DG163 contains four junction-type field-effect transistors designed to function as electronic switches. Level-shifting drivers enable low-level inputs (2 to 3 V) to control the ON-OFF state of the switches. The driver inputs are connected differentially so that with input  $IN_2$  connected to a 2.5 voltage reference, a positive logic "0" at input  $IN_1$  will turn switches 1 and 3 OFF and switches 2 and 4 ON. A positive logic "1" at  $IN_1$  will turn switches 1 and 3 ON and switches 2 and 4 OFF. The normally-grounded  $V_R$  terminal may be used as an "Inhibit" terminal, in which case all switches may be held OFF with a positive voltage applied to  $V_R$ . In the ON state, each switch conducts equally well in either direction, has a series resistance of < 15 ohms, and a shunt leakage of < 2 nA. In the OFF state the switches will hold off voltages up to 15 V peak-to-peak. Switches have make-before-break action. The DG161 is similar to the DG163, except that it contains two FET switches instead of four. It is recommended that the DG186 and DG189 be used for new designs.

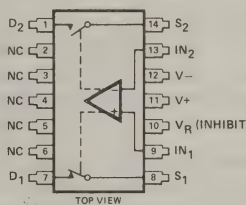
## PIN CONFIGURATIONS



ORDER NUMBERS:  
DG161AL  
SEE PACKAGE 5

LOGIC	SW 1	SW 2
0	OFF	ON
1	ON	OFF

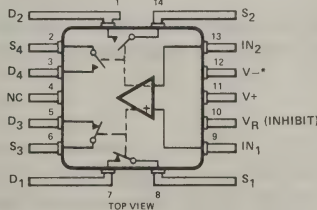
### Dual-In-Line Package



ORDER NUMBERS:  
DG161AP OR DG161BP  
SEE PACKAGE 11

### Flat Package

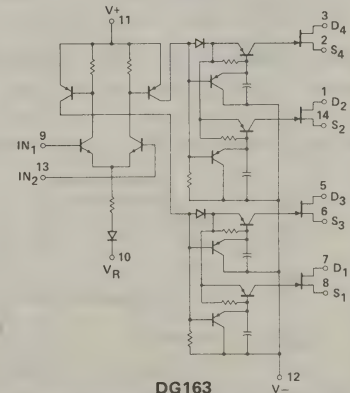
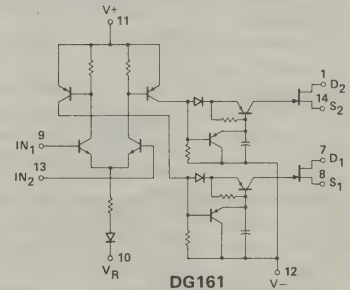
LOGIC	SW 1 SW 3	SW 2 SW 4
0	OFF	ON
1	ON	OFF



ORDER NUMBER: DG163AL  
SEE PACKAGE 5

\*Common to Substrate and Base of Package  
SWITCH STATES ARE FOR  $V_{IN1}$  = LOGIC "1" INPUT AND  
 $V_{IN2}$  = 2.5 V BIAS (POSITIVE LOGIC)

## SCHEMATIC DIAGRAMS





# ABSOLUTE MAXIMUM RATINGS

V+ to V-	36 V	Current (Any Terminal)	30 mA
V+ to VD or VS	36 V	Storage Temperature	-65 to 150°C
VD or VS to V-	32 V	Operating Temperature (A Suffix)	-55 to 125°C
VD to VS	±22 V	(B Suffix)	-20 to 85°C
V+ to VR	25 V	Power Dissipation*	
V+ to VIN1 or VIN2	25 V	Flat Package**	750 mW
VR to V-	25 V	14 Pin DIP***	825 mW
VIN1 to VIN2	±6 V	*All leads welded or soldered to PC board.	
VIN1 or VIN2 to VR	±6 V	**Derate 10 mW/°C above 75°C.	
VIN1 or VIN2 to V-	30 V	***Derate 11 mW/°C above 75°C.	

# ELECTRICAL CHARACTERISTICS

All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC			MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V+ = 15 V, V- = -15 V, VR = 0, VIN2 = 2.5 V*			
			A SUFFIX			B SUFFIX							
			-55 C	25 C	125 C	-20 C	25 C	85 C					
1	S T I T C H	DS(on)	Drain-Source ON Resistance	15	15	30			Ω	VD = 7.5 V	IS = -10 mA VIN1 = 3 V* (SW1,3 ON), VIN1 = 2 V* (SW2,4 ON)		
2							20	20		35		VD = 5.5 V	
3		IS(off)	Source OFF Leakage Current		10	1000			nA	VS = 7.5 V, VD = -7.5 V	VIN1 = 2 V* (SW1,3 OFF), VIN1 = 3 V* (SW2,4 OFF)		
4								15		300		VS = 5.5 V, VD = -5.5 V	
5		ID(off)	Drain OFF Leakage Current		10	1000			VD = 7.5 V, VS = -7.5 V				
6								15	300	VD = 5.5 V, VS = -5.5 V			
7		ID(on) + IS(on)	Channel ON Leakage Current		-2	-100			μA	VD = VS = -7.5 V	VIN1 = 3 V* (SW1,3 ON),		
8										-5	-100	VD = VS = -5.5 V	VIN1 = 2 V* (SW2,4 ON)
9	I N	IIN1L	Input 1 Current, Input 1 Voltage Low	0.1	0.1	2	4	4	4	μA	VIN1 = 2 V*		
10		IIN2L	Input 2 Current, Input 2 Voltage Low	0.1	0.1	2	4	4	4		VIN2 = 2 V*, VIN1 = 2.5 V*		
11		IIN1H	Input 1 Current, Input 1 Voltage High	120	60	60	150	100	100		VIN1 = 3 V*		
12		IIN2H	Input 2 Current, Input 2 Voltage High	120	60	60	150	100	100		VIN2 = 3 V*, VIN1 = 2.5 V*		
13	D Y N A M I C	ton	Turn-ON Time		1			1.5	μs	See Switching Time Test Circuit			
14		toff	Turn-OFF Time		2.5			2.5					
15		CS(off)	Source OFF Capacitance		3 Typ			3 Typ			pF	VS = 0, ID = 0	f = 1 MHz
16		CD(off)	Drain OFF Capacitance		3 Typ			3 Typ				VD = 0, IS = 0	
17	CD(on) + CS(on)	Channel ON Capacitance		2.8 Typ			2.8 Typ		VD = VS = 0				
18	Off Isolation			Typ > 50 dB at 1 MHz**							RL = 100 Ω, CL = 3 pF		
19	S U P P L Y	I+	Positive Supply Current		4			4.4	mA	VIN1 = 2 V* or VIN1 = 3 V*, One Channel ON			
20		I-	Negative Supply Current		-2			-2.2					
21		IR	Reference Supply Current		-2			-2.2					
22		I+	Positive Supply Current		25			25					
23	Y	I-	Negative Supply Current		-25			-25	μA	VIN1 = VIN2 = 0.8 V*, All Channels OFF			
24		IR	Reference Supply Current		-25			-25					

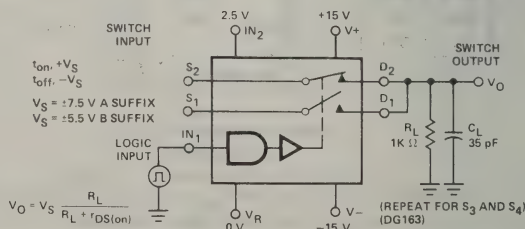
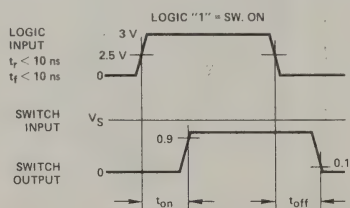
\*VIN1 must be a step function with a minimum rise and fall rate of 1 V/μs.

\*\*Typical values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

LODF + NIP

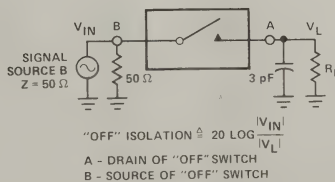
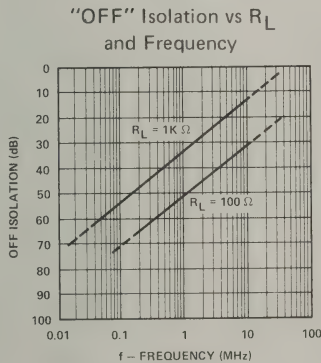
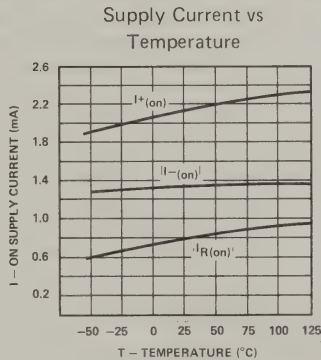
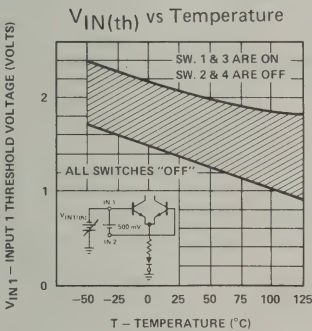
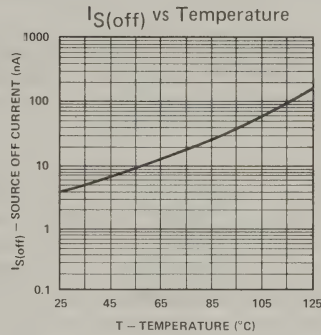
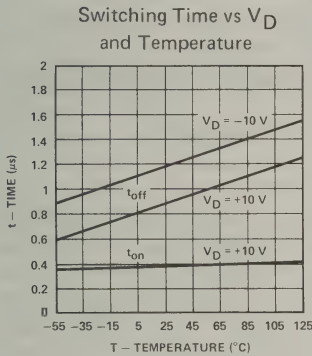
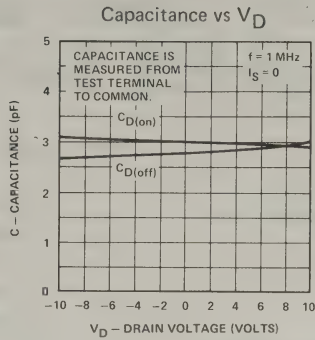
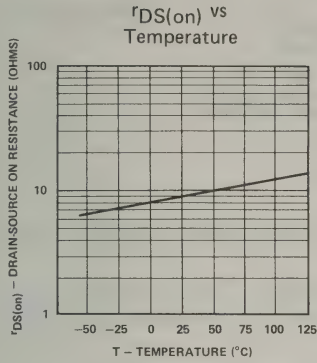
# SWITCHING TIME TEST CIRCUIT

Switch output waveform shown for VS = constant with logic input waveform as shown. Note that VS may be + or - as per switching time test circuit. VO is the steady state output with switch on. Feedthrough via gate capacitance may result in spikes at leading and trailing edge of output waveform.

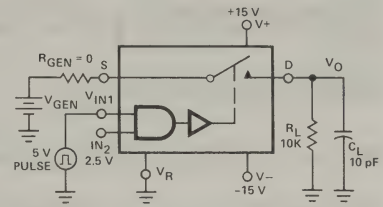




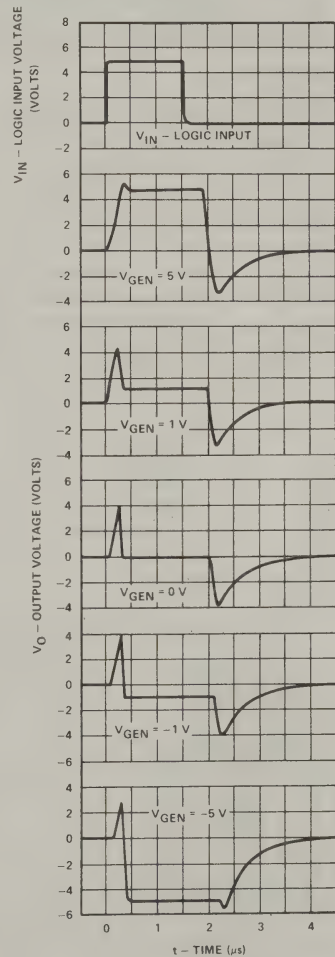
# TYPICAL CHARACTERISTICS



Typical delay, rise, fall, settling times, and switching transients in this circuit.



If  $R_{GEN}$ ,  $R_L$  or  $C_L$  is increased, there will be proportional increases in rise and/or fall RC times.



# Drivers with Differentially Driven Normally Open and Normally Closed FET Switches designed for . . .



- **Switching High Frequencies**
- **Switching in Satellite Applications**
- **Portable, Battery Operated Circuits**
- **Low Signal Distortion Switching Circuits such as Audio Switching**

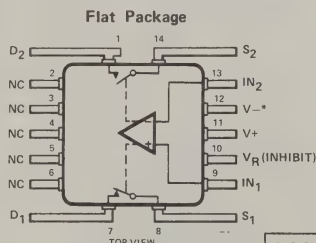
## BENEFITS

- **Higher Signal Bandwidth Switching Capabilities**
  - OFF Isolation > 60 dB @ 1 MHz
- **Better Radiation Resistance than PMOS Drivers**
  - Bipolar Drivers
- **Minimizes Standby Power Requirements**
  - < 1 mW Standby Power
- **Less Signal Distortion than CMOS or PMOS Switches**
  - Constant ON Resistance

## DESCRIPTION

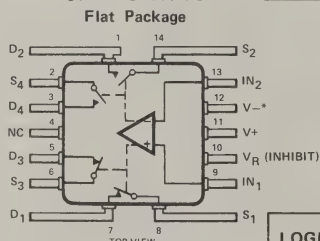
The DG164 contains four junction-type field-effect transistors designed to function as electronic switches. Level-shifting drivers enable low-level inputs (2 to 3 V) to control the ON-OFF state of the switches. The driver inputs are connected differentially so that with input  $IN_2$  connected to a 2.5 voltage reference, a positive logic "0" at input  $IN_1$  will turn switches 1 and 3 OFF and switches 2 and 4 ON. A positive logic "1" at  $IN_1$  will turn switches 1 and 3 ON and switches 2 and 4 OFF. The normally-grounded  $V_R$  terminal may be used as an "Inhibit" terminal, in which case all switches may be held OFF with a positive voltage applied to  $V_R$ . In the ON state, each switch conducts equally well in either direction, has a series resistance of < 50 ohms, and a shunt leakage of < 2 nA. In the OFF state the switches will hold off voltages up to 15 V peak-to-peak. Switches have make-before-break action. The DG162 is similar to the DG164, except that it contains two FET switches instead of four. It is recommended that the DG187 (or DG188) and DG190 (or DG191) be used for new designs.

## PIN CONFIGURATIONS



ORDER NUMBER:  
DG162AL  
SEE PACKAGE 5

LOGIC	SW 1	SW 2
0	OFF	ON
1	ON	OFF



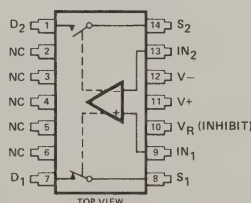
ORDER NUMBER:  
DG164AL  
SEE PACKAGE 5

LOGIC	SW 1 SW 3	SW 2 SW 4
0	OFF	ON
1	ON	OFF

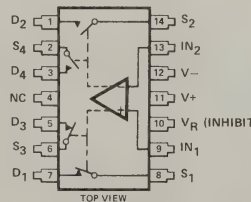
\* Common to Substrate and Base of Package

SWITCH STATES ARE FOR  $V_{IN1}$  = LOGIC "1" INPUT AND  
 $V_{IN2}$  = 2.5 V BIAS (POSITIVE LOGIC)

## Dual-In-Line Package

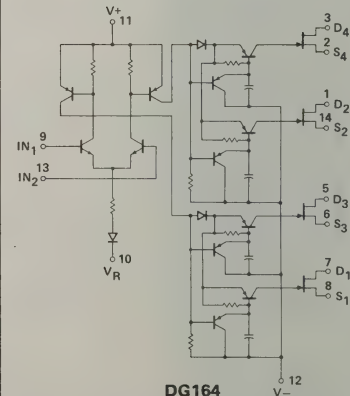
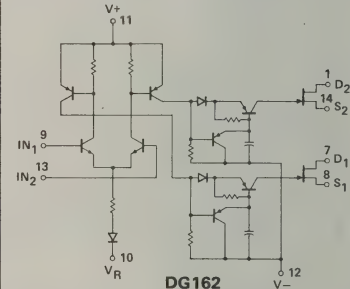


ORDER NUMBERS:  
DG162AP OR DG162BP  
SEE PACKAGE 11  
Dual-In-Line Package



ORDER NUMBERS:  
DG164AP OR DG164BP  
SEE PACKAGE 11

## SCHEMATIC DIAGRAMS



# ABSOLUTE MAXIMUM RATINGS

V+ to V-	36 V
V+ to VD or VS	36 V
VD or VS to V-	36 V
VD to VS	±22 V
V+ to VR	25 V
V+ to VIN1 or VIN2	25 V
VR to V-	25 V
VIN1 to VIN2	±6 V
VIN1 or VIN2 to VR	±6 V
VIN1 or VIN2 to V-	30 V

Current (Any Terminal)	30 mA
Storage Temperature	-65 to 150°C
Operating Temperature (A Suffix)	-55 to 125°C
(B Suffix)	-20 to 85°C
Power Dissipation*	
Flat Package**	750 mW
14 Pin DIP***	825 mW
*All leads welded or soldered to PC board.	
**Derate 10 mW/°C above 75°C.	
***Derate 11 mW/°C above 75°C.	

**ELECTRICAL CHARACTERISTICS** All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

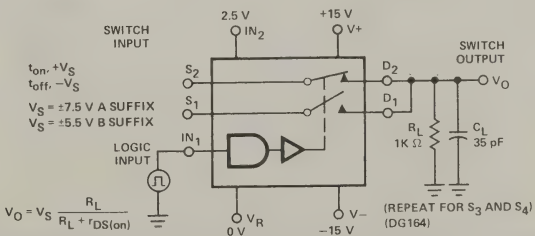
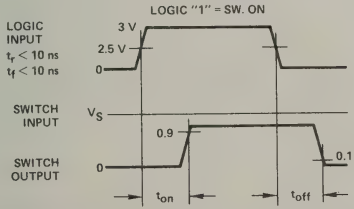
CHARACTERISTIC			MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V+ = 15 V, V- = -15 V, VR = 0, VIN2 = 2.5 V*		
			A SUFFIX			B SUFFIX						
			-55°C	25°C	125°C	-20°C	25°C	85°C				
1	fDS(on)	Drain-Source ON Resistance	50	50	100				Ω	VD = 7.5 V	IS = -10 mA VIN1 = 3 V* (SW1,3 ON), VIN1 = 2 V* (SW2,4 ON)	
2						100	100	150		VD = 5.5 V		
3	IS(off)	Source OFF Leakage Current		2	100				nA	VS = 7.5 V, VD = -7.5 V		VIN1 = 2 V* (SW1,3 OFF), VIN1 = 3 V* (SW2,4 OFF)
4							5	100		VS = 5.5 V, VD = -5.5 V		
5	ID(off)	Drain OFF Leakage Current		2	100					VD = 7.5 V, VS = -7.5 V		
6							5	100			VD = 5.5 V, VS = -5.5 V	
7	ID(on) + IS(on)	Channel ON Leakage Current		-2	100				μA	VD = VS = -7.5 V	VIN1 = 3 V* (SW1,3 ON) VIN1 = 2 V* (SW2,4 ON)	
8							-5	100		VD = VS = -5.5 V		
9	IIN1L	Input 1 Current, Input 1 Voltage Low	0.1	0.1	2	4	4	4	μA	VIN1 = 2 V*		
10		Input 2 Current, Input 2 Voltage Low	0.1	0.1	2	4	4	4		VIN2 = 2 V*, VIN1 = 2.5 V*		
11		Input 1 Current, Input 1 Voltage High	120	60	60	150	100	100		VIN1 = 3 V*		
12		Input 2 Current, Input 2 Voltage High	120	60	60	150	100	100		VIN2 = 3 V*, VIN1 = 2.5 V*		
13	ton	Turn-ON Time		0.8			1		μs	See Switching Time Test Circuit		
14	toff	Turn-OFF Time		1.6			2					
15	CS(off)	Source OFF Capacitance		2.4 Typ			2.4 Typ		pF	VS = 0, ID = 0	f = 1 MHz	
16		CD(off)	Drain OFF Capacitance		2.4 Typ		2.4 Typ			VD = 0, IS = 0		
17		CD(on) + CS(on)	Channel ON Capacitance		2.8 Typ			2.8 Typ				VD = VS = 0
18	Off Isolation		Typ > 60 dB at 1 MHz**							RL = 75 Ω		
19	ISUPPLY	Positive Supply Current		4			4.4		mA	VIN1 = 2 V* or VIN1 = 3 V*, One Channel ON		
20		Negative Supply Current		-2			-2.2					
21		IR	Reference Supply Current		-2			-2.2		μA	VIN1 = VIN2 = 0.8 V*, All Channels OFF	
22		I+	Positive Supply Current		25			25				
23	IR	Negative Supply Current		-25			-25		μA			
24			Reference Supply Current		-25			-25				

\*VIN must be a step function with a minimum rise and fall rate of 1 V/μs.  
\*\*Typical values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

LODF + NC

## SWITCHING TIME TEST CIRCUIT

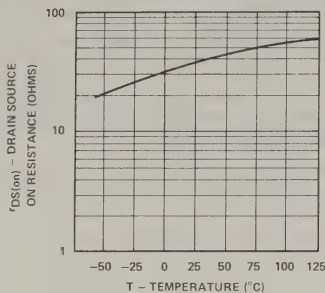
Switch output waveform shown for VS = constant with logic input waveform as shown. Note that VS may be + or - as per switching time test circuit. VO is the steady state output with switch on. Feedthrough via gate capacitance may result in spikes at leading and trailing edge of output waveform.



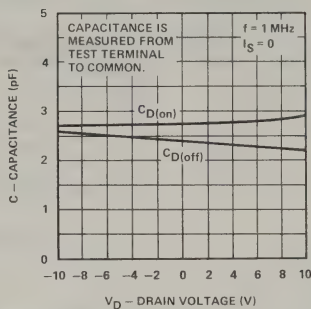


# TYPICAL CHARACTERISTICS

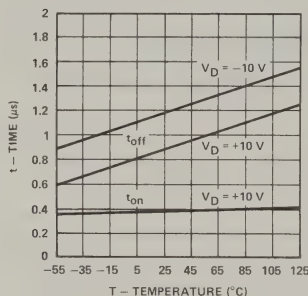
$r_{DS(on)}$  vs Temperature



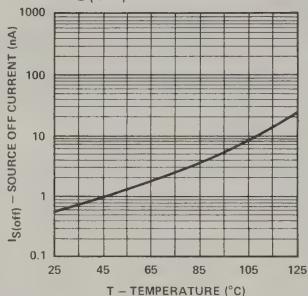
Capacitance vs  $V_D$



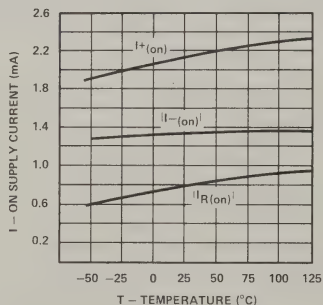
Switching Time vs  $V_D$  and Temperature



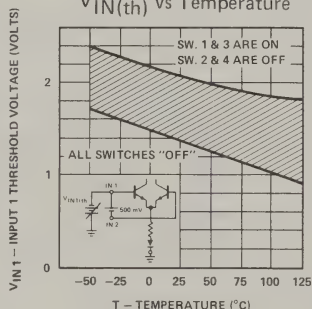
$I_{S(off)}$  vs Temperature



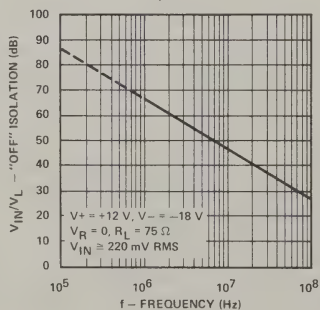
Supply Current vs Temperature



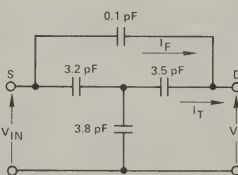
$V_{IN(th)}$  vs Temperature



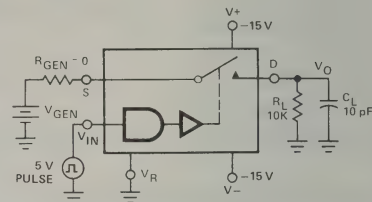
"OFF" Isolation vs  $R_L$  and Frequency



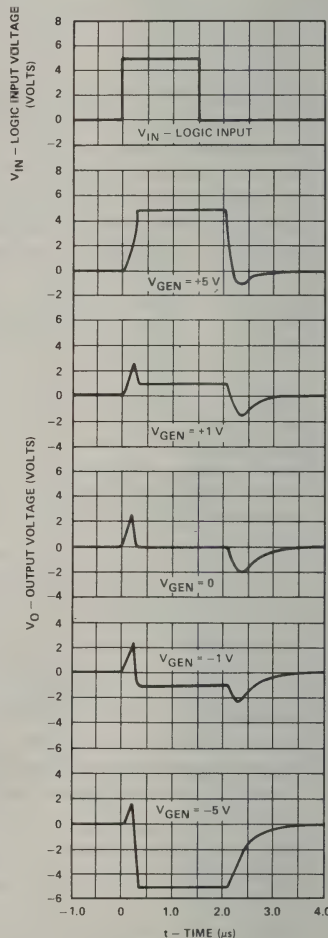
Equivalent "OFF" Circuit



Typical delay, rise, fall, settling times, and switching transients in this circuit.



If  $R_{GEN}$ ,  $R_L$  or  $C_L$  is increased, there will be proportional increases in rise and/or fall RC times.





# Monolithic 4-Channel Driver with PMOS Switches



DG172

*designed for . . .*

- **Make-Before-Break Switching**  
**i.e. Feedback Resistor Switching**  
**in Variable Gain Op-Amps**
- **Low Leakage Switching such**  
**as Sample and Hold Circuits**

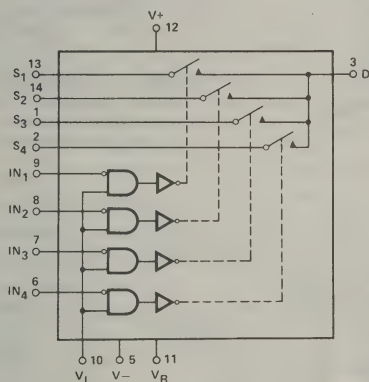
## BENEFITS

- **Easily Interfaced**
  - TTL, CMOS, DTL Direct Drive Compatibility
- **Reduces External Component Requirements**
  - No Interface Components Required
  - Voltage-Limiting Diodes Protect PMOS Gates

## DESCRIPTION

The DG172 contains four MOS field-effect transistors designed to function as electronic switches. Level-shifting drivers enable a low-level input (0.8 to 2.0 V) to control the ON-OFF condition of each switch. In the ON state, each switch will conduct current equally well in either direction. In the OFF state, the switches will block voltages up to 20 V peak-to-peak. Positive logic "0" at the driver input will turn each switch ON. A common driver terminal  $V_L$  may be used to clock all four switches by switching the device from the ENABLE mode ( $\geq 4$  V) to the INHIBIT mode ( $\leq 0.4$  V).

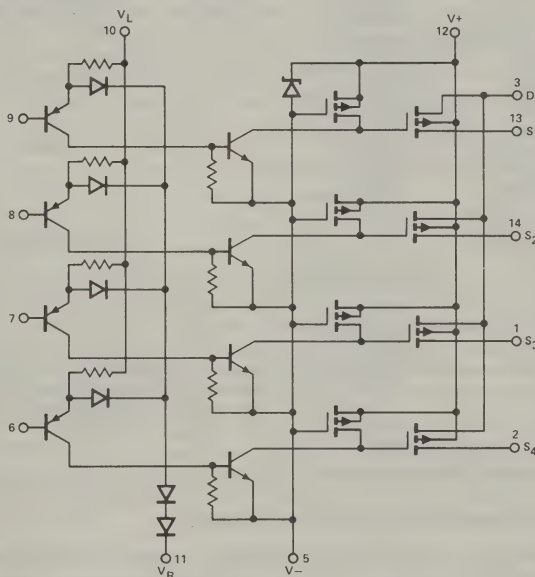
## FUNCTIONAL DIAGRAM



LOGIC	SWITCH
0	ON
1	OFF

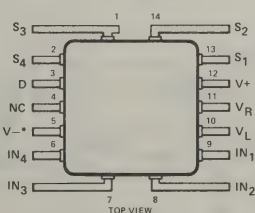
SWITCH STATES ARE FOR LOGIC "1" INPUT.  
(POSITIVE LOGIC)

## SCHEMATIC DIAGRAM



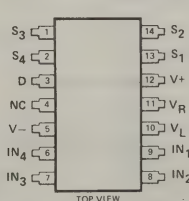
## PIN CONFIGURATIONS

Flat Package



ORDER NUMBER: DG172AL  
SEE PACKAGE 5

Dual-In-Line Package



ORDER NUMBERS: DG172AP OR DG172BP  
SEE PACKAGE 11

DG172CJ

SEE PACKAGE 7

\* Common to Substrate and Base of Package

3  
Analog Switches

# ABSOLUTE MAXIMUM RATINGS

V <sup>+</sup> to V <sup>-</sup> . . . . .	36 V	Operating Temperature (A Suffix) . . . . .	-55 to 125°C
V <sup>+</sup> to V <sub>D</sub> . . . . .	25 V	(B Suffix) . . . . .	-20 to 85°C
V <sup>+</sup> to V <sub>S</sub> . . . . .	25 V	(C Suffix) . . . . .	0 to 70°C
V <sub>S</sub> to V <sup>-</sup> . . . . .	36 V	Power Dissipation* . . . . .	
V <sub>D</sub> to V <sup>-</sup> . . . . .	36 V	Flat Package** . . . . .	750 mW
V <sub>S</sub> to V <sub>D</sub> . . . . .	25 V	14 Pin DIP (ceramic)*** . . . . .	825 mW
V <sub>L</sub> to V <sup>-</sup> . . . . .	30 V	14 Pin Plastic DIP**** . . . . .	470 mW
V <sub>L</sub> to V <sub>IN</sub> . . . . .	±6 V	*All leads welded or soldered to PC board	
V <sub>L</sub> to V <sub>R</sub> . . . . .	±6 V	**Derate 10 mW/°C above 75°C	
V <sub>IN</sub> to V <sub>R</sub> . . . . .	±6 V	***Derate 11 mW/°C above 75°C	
Current (Any Terminal) . . . . .	20 mA	****Derate 6.3 mW/°C above 25°C	
Storage Temperature (A & B Suffix) . . . . .	-65 to 150°C		
(C Suffix) . . . . .	-65 to 125°C		

# ELECTRICAL CHARACTERISTICS

All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

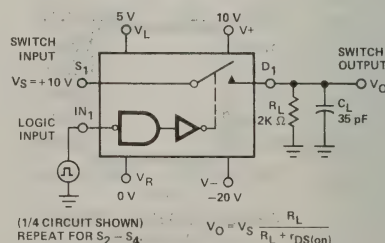
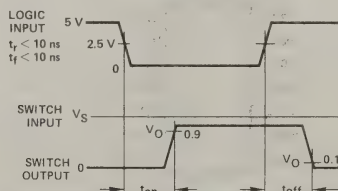
CHARACTERISTIC			MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V <sup>+</sup> = 10 V, V <sup>-</sup> = -20 V, V <sub>L</sub> = 5 V, V <sub>R</sub> = 0			
			DG172A			DG172B		DG172C					
			-55° C	25° C	125° C	-20° C	25° C	85° C	25° C				
1	S	D <sub>S(on)</sub> Drain-Source ON Resistance	150	150	250	150	150	200	200	Ω	V <sub>D</sub> = 10 V	I <sub>S</sub> = -1 mA V <sub>IN</sub> = 0.8 V	
2			200	200	350	225	225	300	300		V <sub>D</sub> = 0		
3			450	450	600	500	500	600	600		V <sub>D</sub> = -10 V		
4	I	S <sub>OFF</sub> Source OFF Leakage Current		-1	-1000		-5	-100	-10	nA	V <sub>S</sub> = -10 V, V <sub>D</sub> = 10 V	V <sub>IN</sub> = 2 V	
5			D <sub>OFF</sub> Drain OFF Leakage Current		-4	-4000		-10	-300		-10		V <sub>D</sub> = -10 V, V <sub>S</sub> = 10 V
6			I <sub>D(on)</sub> + I <sub>S(on)</sub> Channel ON Leakage Current		4	4000		10	300		10		V <sub>D</sub> = V <sub>S</sub> = 10 V
7	I	I <sub>INL</sub> Input Current, Input Voltage Low	-0.5	-0.5	-0.5	-1	-1	-1	-1	mA	V <sub>IN</sub> = 0		
8			I <sub>INH</sub> Input Current, Input Voltage High	0.1	0.1	10	0.1	1	10		1		V <sub>IN</sub> = 5 V
9			t <sub>on</sub> Turn-ON Time		0.3			0.5			0.08 Typ*		
10	D	t <sub>off</sub> Turn-OFF Time		0.75			1		0.5 Typ*	μs	See Switching Time Test Circuit		
11			C <sub>S(off)</sub> Source OFF Capacitance	5 Typical*							pF	V <sub>S</sub> = 0, I <sub>D</sub> = 0	f = 1 MHz
12			C <sub>D(off)</sub> Drain OFF Capacitance	18 Typical*								V <sub>D</sub> = 0, I <sub>S</sub> = 0	
13	C <sub>D(on)</sub> + C <sub>S(on)</sub> Channel ON Capacitance	28 Typical*						V <sub>D</sub> = V <sub>S</sub> = 0					
14	Off Isolation		Typ > 50 dB at 5 MHz*								R <sub>L</sub> = 100 Ω, C <sub>L</sub> = 3 pF		
15	S	I <sup>+</sup> Positive Supply Current		3				3		mA	I <sub>R</sub> = 0	V <sub>IN</sub> = 0, One Channel ON	
16			I <sup>-</sup> Negative Supply Current		-5.1			-5.1					-5.1
17			I <sub>L</sub> Logic Supply Current		5.7			5.7					5.7
18	U	I <sub>R</sub> Reference Supply Current		2.1			2.1		2.1	μA			
19					-3.6			-3.6					-3.6
20			I <sup>+</sup> Positive Supply Current		10			10					10
21	P	I <sup>-</sup> Negative Supply Current		-20			-20		-20	mA		V <sub>IN</sub> = 5 V, All Channels OFF	
22			I <sub>L</sub> Logic Supply Current		4.5			4.5					4.5
23					10			10					10
24	L	I <sub>R</sub> Reference Supply Current		-4.5			-4.5		-4.5	mA	I <sub>R</sub> = 0		

\*Typical Values are for DESIGN AID ONLY, not guaranteed and not subject to production testing

CMD

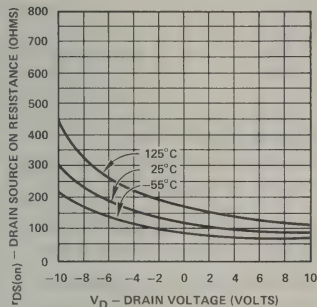
# SWITCHING TIME TEST CIRCUIT

Switch output waveform shown for V<sub>S</sub> = constant with logic input waveform as shown. Note that V<sub>S</sub> may be + or - as per switching time test circuit. V<sub>O</sub> is the steady state output with switch on. Feedthrough via gate capacitance may result in spikes at leading and trailing edge of output waveform.

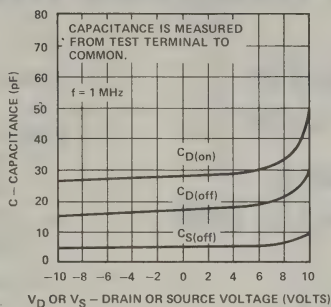


# TYPICAL CHARACTERISTICS

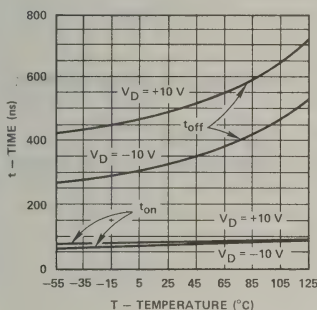
$r_{DS(on)}$  vs  $V_D$  and Temperature



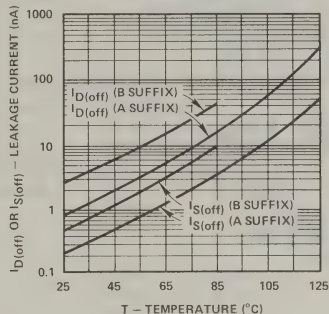
Capacitance vs  $V_D$  or  $V_S$



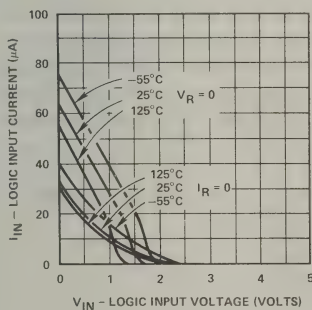
Switching Time vs  $V_D$  and Temperature



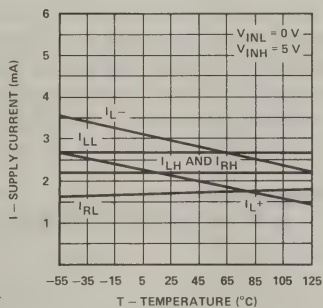
$I_{D(off)}/I_{S(off)}$  vs Temperature



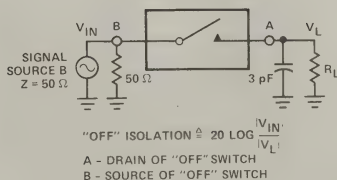
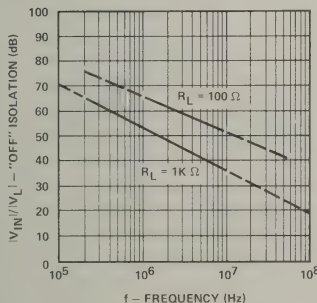
$I_{IN}$  vs  $V_{IN}$  and Temperature



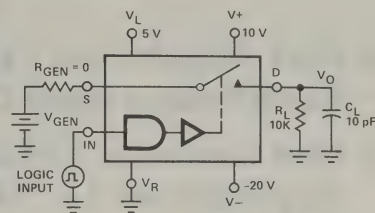
Supply Current vs Temperature



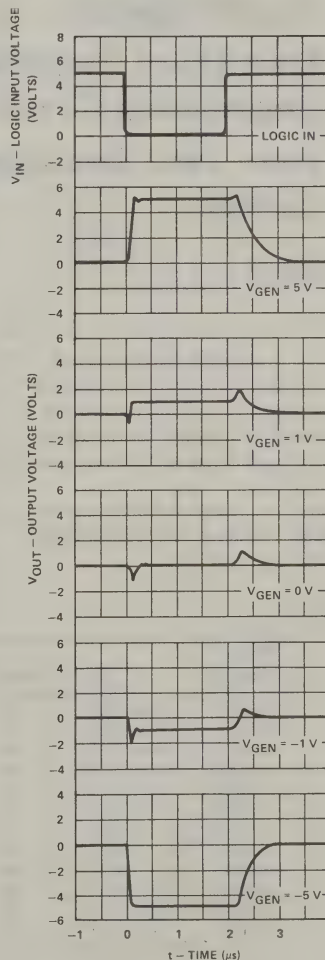
"OFF" Isolation vs  $R_L$  and Frequency



Typical delay, rise, fall, settling times, and switching transients in this circuit.



If  $R_{GEN}$ ,  $R_L$  or  $C_L$  is increased, there will be proportional increases in rise and/or fall RC times.





# High-Speed Driver with JFET Switches *designed for...*



- **Fast Acquisition Speed in Sample and Hold Circuits**
- **Low Leakage Switching Applications i.e. Sample and Hold Circuits**
- **High Frequency Signal Switching such as Video Signals**
- **Low Distortion Switching, Audio Signals**
- **Low Level Switching in Low Impedance Circuits**
- **Fast, Low Resistance D/A Ladders**

## BENEFITS

- **Eliminates Large Signal Error**
  - $< 2$  nA Leakage from Signal Channel in Both ON and OFF States
- **Increased Current Handling Capabilities**
  - 200 mA Maximum Switching Current
- **Higher Bandwidth Switching Capabilities**
  - Cross-Talk and OFF Isolation  $> 55$  dB at 1 MHz (75  $\Omega$  Load)
- **Easily Interfaced**
  - TTL, DTL, RTL Direct Drive Compatibility
- **Less Signal Distortion than CMOS or PMOS Switches**
  - Constant ON Resistance
- **Low Voltage Drop Across Switch in the ON State**
  - $r_{ds(on)} \leq 10 \Omega$

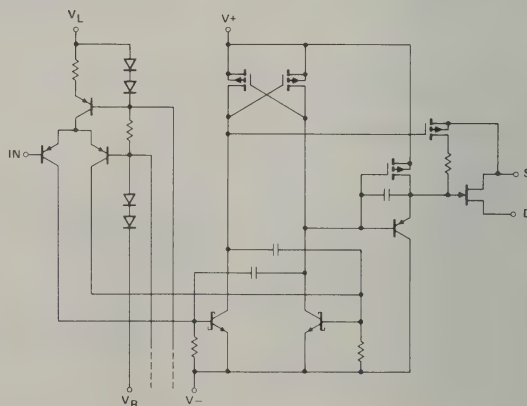
## DESCRIPTION

The DG180 series contains two to four N-channel junction-type field-effect transistors (JFET) designed to function as electronic switches. Level-shifting drivers enable low-level inputs (0.8 to 2.0 V) to control the ON-OFF state of each switch. The driver is designed to provide a turn-off speed which is faster than turn-on speed, so that break-before-make action is achieved when switching from one channel to another. In the ON state each switch conducts current equally well in either direction. In the OFF condition the switches will block voltages up to 20 V peak-to-peak. Switch-OFF input-output feed-through is  $> 60$  dB at 10 MHz, because of the low output impedance of the FET-gate driving circuit.

## FUNCTIONAL DESCRIPTION

PART NUMBER	TYPE	$R_{ON}$ (MAX)
DG180	Dual SPST	10
DG181	Dual SPST	30
DG182	Dual SPST	75
DG183	Dual DPST	10
DG184	Dual DPST	30
DG185	Dual DPST	75
DG186	SPDT	10
DG187	SPDT	30
DG188	SPDT	75
DG189	Dual SPDT	10
DG190	Dual SPDT	30
DG191	Dual SPDT	75

## SCHEMATIC DIAGRAM (Typical Channel)



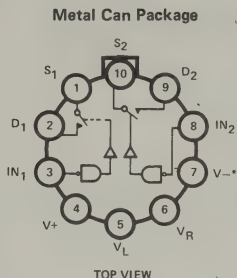


# PIN CONFIGURATIONS

## DUAL SPST

LOGIC	SWITCH
0	ON
1	OFF

SWITCH STATES ARE  
FOR LOGIC "1" INPUT  
(POSITIVE LOGIC)

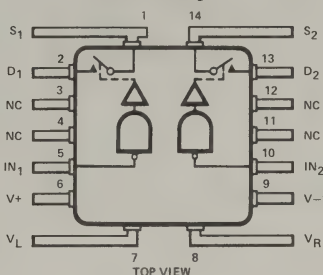


TOP VIEW

ORDER NUMBERS:  
DG180AA OR DG180BA  
DG181AA OR DG181BA  
DG182AA OR DG182BA  
SEE PACKAGE 2

\*Common to Substrate and Case

## Flat Package

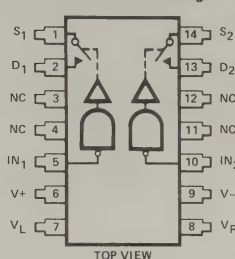


TOP VIEW

ORDER NUMBER:  
DG181AL  
SEE PACKAGE 5

\*Common to Substrate and Base of Package

## Dual-In-Line Package



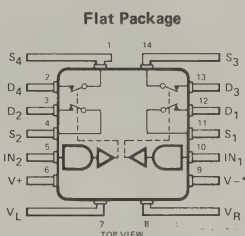
TOP VIEW

ORDER NUMBERS:  
DG180AP OR DG180BP  
DG181AP OR DG181BP  
DG182AP OR DG182BP  
SEE PACKAGE 11

## DUAL DPST

LOGIC	SWITCH
0	OFF
1	ON

SWITCH STATES ARE  
FOR LOGIC "1" INPUT  
(POSITIVE LOGIC)

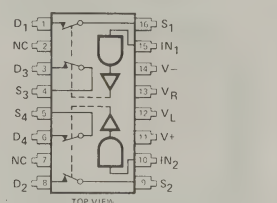


TOP VIEW

ORDER NUMBERS:  
DG184AL OR DG185AL  
SEE PACKAGE 5

\*Common to Substrate and Base of Package

## Dual-In-Line Package



TOP VIEW

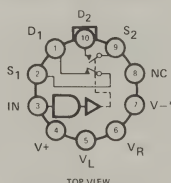
ORDER NUMBERS:  
DG183AP OR DG183BP  
DG184AP OR DG184BP  
DG185AP OR DG185BP  
SEE PACKAGE 12

## SPDT

LOGIC	SW 1	SW 2
0	OFF	ON
1	ON	OFF

SWITCH STATES ARE  
FOR LOGIC "1" INPUT  
(POSITIVE LOGIC)

## Metal Can Package

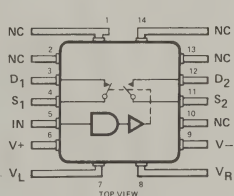


TOP VIEW

ORDER NUMBERS:  
DG186AA OR DG186BA  
DG187AA OR DG187BA  
DG188AA OR DG188BA  
SEE PACKAGE 2

\*Common to Substrate and Case

## Flat Package

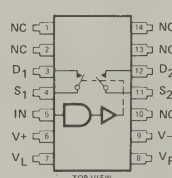


TOP VIEW

ORDER NUMBERS:  
DG187AL OR DG188AL  
SEE PACKAGE 5

\*Common to Substrate and Base of Package

## Dual-In-Line Package



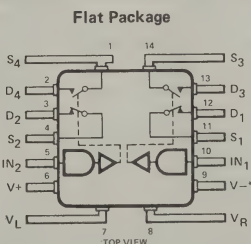
TOP VIEW

ORDER NUMBERS:  
DG186AP OR DG186BP  
DG187AP OR DG187BP  
DG188AP OR DG188BP  
SEE PACKAGE 11

## DUAL SPDT

LOGIC	SW 1 SW 2	SW 3 SW 4
0	OFF	ON
1	ON	OFF

SWITCH STATES ARE  
FOR LOGIC "1" INPUT  
(POSITIVE LOGIC)

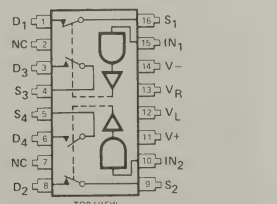


TOP VIEW

ORDER NUMBERS:  
DG190AL OR DG191AL  
SEE PACKAGE 5

\*Common to Substrate and Base of Package

## Dual-In-Line Package



TOP VIEW

ORDER NUMBERS:  
DG189AP OR DG189BP  
DG190AP OR DG190BP  
DG191AP OR DG191BP  
SEE PACKAGE 12

# ABSOLUTE MAXIMUM RATINGS

V <sub>+</sub> to V <sub>-</sub>	36 V
V <sub>+</sub> to V <sub>D</sub>	33 V
V <sub>D</sub> to V <sub>-</sub>	33 V
V <sub>D</sub> to V <sub>S</sub>	±22 V
V <sub>L</sub> to V <sub>-</sub>	36 V
V <sub>L</sub> to V <sub>IN</sub>	8 V
V <sub>L</sub> to V <sub>R</sub>	8 V
V <sub>IN</sub> to V <sub>R</sub>	8 V
V <sub>R</sub> to V <sub>-</sub>	27 V
V <sub>R</sub> to V <sub>IN</sub>	2 V
Current (Any Terminal except S or D)	30 mA

Currents (S or D) 30 Ω, 75 Ω	30 mA
10 Ω Only	200 mA
Storage Temperature	-65 to 150°C
Operating Temperature (A Suffix)	-55 to 125°C
(B Suffix)	-20 to 85°C

## Power Dissipation\*

Metal Can**	450 mW
14 Pin DIP***	825 mW
16 Pin DIP****	900 mW
Flat Pack*****	900 mW

\*All leads welded or soldered to PC board.

\*\*Derate 6 mW/°C above 75°C.

\*\*\*Derate 11 mW/°C above 75°C.

\*\*\*\*Derate 12 mW/°C above 75°C.

\*\*\*\*\*Derate 10 mW/°C above 75°C.

**ELECTRICAL CHARACTERISTICS** All DC parameters are 100% tested at 25°C. Lots are sample tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC		MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V <sub>+</sub> = 15 V, V <sub>-</sub> = -15 V, V <sub>L</sub> = 5 V, V <sub>R</sub> = 0					
		A SUFFIX			B SUFFIX									
		-55°C	25°C	125°C	-20°C	25°C	85°C							
10 Ω	S W I T C H	1	r <sub>DS(on)</sub>	Drain-Source ON Resistance	10	10	20	15	15	25	Ω	V <sub>D</sub> = -7.5 V	I <sub>S</sub> = -10 mA V <sub>IN</sub> = 0.8 V or 2.0 V	Note 1
		2	I <sub>S(off)</sub>	Source OFF Leakage Current		10	1000		15	300	nA	V <sub>S</sub> = 10 V, V <sub>D</sub> = -10 V V <sub>+</sub> = 10 V, V <sub>-</sub> = -20 V	V <sub>IN</sub> = 2.0 V or 0.8 V Note 2	
		3	I <sub>D(off)</sub>	Drain OFF Leakage Current		10	1000		15	300	nA	V <sub>S</sub> = 7.5 V, V <sub>D</sub> = -7.5 V		
		4	I <sub>D(on)</sub> + I <sub>S(on)</sub>	Channel ON Leakage Current		10	1000		15	300	nA	V <sub>D</sub> = 10 V, V <sub>S</sub> = -10 V V <sub>+</sub> = 10 V, V <sub>-</sub> = -20 V		
		5	I <sub>DSS</sub>	Saturation Drain Current		-2	-200		-10	-200	nA	V <sub>D</sub> = 7.5 V, V <sub>S</sub> = -7.5 V		
		6	I <sub>DSS</sub>	Saturation Drain Current			300 Typical*				mA	V <sub>D</sub> = V <sub>S</sub> = -7.5 V		
	D Y N A M I C	7	I <sub>INL</sub>	Input Current, Input Voltage Low	-250	-250	-250	-250	-250	-250	μA	V <sub>IN</sub> = 0	f = 1 MHz	
		8	I <sub>INH</sub>	Input Current, Input Voltage High		10	20		10	20	μA	V <sub>IN</sub> = 5 V		
		9	t <sub>on</sub>	Turn-ON Time		300			350	ns	See Switching Time Test Circuit			
		10	t <sub>off</sub>	Turn-OFF Time		250			300	ns	See Switching Time Test Circuit			
		11	C <sub>S(off)</sub>	Source OFF Capacitance			21 Typical*				pF	V <sub>S</sub> = -5 V, I <sub>D</sub> = 0		
		12	C <sub>D(off)</sub>	Drain OFF Capacitance			17 Typical*				pF	V <sub>D</sub> = 5 V, I <sub>S</sub> = 0		
		13	C <sub>D(on)</sub> + C <sub>S(on)</sub>	Channel ON Capacitance			17 Typical*				pF	V <sub>D</sub> = V <sub>S</sub> = 0		
		14		OFF Isolation			Typical > 55 dB at 1 MHz *					R <sub>L</sub> = 75 Ω		
		30 Ω	S W I T C H	1	r <sub>DS(on)</sub>	Drain-Source ON Resistance	30	30	60	50	50	75	Ω	V <sub>D</sub> = -7.5 V
2	I <sub>S(off)</sub>			Source OFF Leakage Current		1	100		5	100	nA	V <sub>S</sub> = 10 V, V <sub>D</sub> = -10 V V <sub>+</sub> = 10 V, V <sub>-</sub> = -20 V	V <sub>IN</sub> = 2.0 V or 0.8 V Note 2	
3	I <sub>D(off)</sub>			Drain OFF Leakage Current		1	100		5	100	nA	V <sub>S</sub> = 7.5 V, V <sub>D</sub> = -7.5 V		
4	I <sub>D(on)</sub> + I <sub>S(on)</sub>			Channel ON Leakage Current		1	100		5	100	nA	V <sub>D</sub> = 10 V, V <sub>S</sub> = -10 V V <sub>+</sub> = 10 V, V <sub>-</sub> = -20 V		
5	I <sub>DSS</sub>			Saturation Drain Current		-2	-200		-10	-200	nA	V <sub>D</sub> = 7.5 V, V <sub>S</sub> = -7.5 V		
6	I <sub>DSS</sub>			Saturation Drain Current			9 Typical*				mA	V <sub>D</sub> = V <sub>S</sub> = -7.5 V		
D Y N A M I C	7		I <sub>INL</sub>	Input Current, Input Voltage Low	-250	-250	-250	-250	-250	-250	μA	V <sub>IN</sub> = 0	f = 1 MHz	
	8		I <sub>INH</sub>	Input Current, Input Voltage High		10	20		10	20	μA	V <sub>IN</sub> = 5 V		
	9		t <sub>on</sub>	Turn-ON Time		150			180	ns	See Switching Time Test Circuit			
	10		t <sub>off</sub>	Turn-OFF Time		130			150	ns	See Switching Time Test Circuit			
	11		C <sub>S(off)</sub>	Source OFF Capacitance			9 Typical*				pF	V <sub>S</sub> = -5 V, I <sub>D</sub> = 0		
	12		C <sub>D(off)</sub>	Drain OFF Capacitance			6 Typical*				pF	V <sub>D</sub> = -5 V, I <sub>S</sub> = 0		
	13		C <sub>D(on)</sub> + C <sub>S(on)</sub>	Channel ON Capacitance			14 Typical*				pF	V <sub>D</sub> = V <sub>S</sub> = 0		
	14			OFF Isolation			Typical > 50 dB at 10 MHz					R <sub>L</sub> = 75 Ω		
	75 Ω		S W I T C H	1	r <sub>DS(on)</sub>	Drain-Source ON Resistance	75	75	150	100	100	150	Ω	V <sub>D</sub> = -10 V
2		I <sub>S(off)</sub>		Source OFF Leakage Current		1	100		5	100	nA	V <sub>S</sub> = 10 V, V <sub>D</sub> = -10 V V <sub>+</sub> = 10 V, V <sub>-</sub> = -20 V	V <sub>IN</sub> = 2.0 V or 0.8 V Note 2	
3		I <sub>D(off)</sub>		Drain OFF Leakage Current		1	100		5	100	nA	V <sub>S</sub> = 10 V, V <sub>D</sub> = -10 V		
4		I <sub>D(on)</sub> + I <sub>S(on)</sub>		Channel ON Leakage Current		1	100		5	100	nA	V <sub>D</sub> = 10 V, V <sub>S</sub> = -10 V V <sub>+</sub> = 10 V, V <sub>-</sub> = -20 V		
5		I <sub>DSS</sub>		Saturation Drain Current		-2	-200		-10	-200	nA	V <sub>D</sub> = 10 V, V <sub>S</sub> = -10 V		
6		I <sub>DSS</sub>		Saturation Drain Current			9 Typical*				mA	V <sub>D</sub> = V <sub>S</sub> = -10 V		
D Y N A M I C		7	I <sub>INL</sub>	Input Current, Input Voltage Low	-250	-250	-250	-250	-250	-250	μA	V <sub>IN</sub> = 0	f = 1 MHz	
		8	I <sub>INH</sub>	Input Current, Input Voltage High		10	20		10	20	μA	V <sub>IN</sub> = 5 V		
		9	t <sub>on</sub>	Turn-ON Time		250			300	ns	See Switching Time Test Circuit			
		10	t <sub>off</sub>	Turn-OFF Time		130			150	ns	See Switching Time Test Circuit			
		11	C <sub>S(off)</sub>	Source OFF Capacitance			9 Typical*				pF	V <sub>S</sub> = -5 V, I <sub>D</sub> = 0		
		12	C <sub>D(off)</sub>	Drain OFF Capacitance			6 Typical*				pF	V <sub>D</sub> = -5 V, I <sub>S</sub> = 0		
		13	C <sub>D(on)</sub> + C <sub>S(on)</sub>	Channel ON Capacitance			14 Typical*				pF	V <sub>D</sub> = V <sub>S</sub> = 0		
		14		OFF Isolation			Typical > 50 dB at 10 MHz					R <sub>L</sub> = 75 Ω		

NOTES: 1. V<sub>IN</sub> = 0.8 V or 2.0 V to turn ON switch under test. 2. V<sub>IN</sub> = 0.8 V or 2.0 V to turn OFF switch under test.

# ELECTRICAL CHARACTERISTICS Power Supply Current (25°C)

CHARACTERISTIC	A OR B SUFFIX MAX LIMITS				UNIT	TEST CONDITIONS, UNLESS NOTED: V+ = 15 V, V- = -15 V, V <sub>L</sub> = 5 V, V <sub>R</sub> = 0
	DG180, DG181 DG182, DG189 DG190, DG191	DG183 DG184 DG185	DG186 DG187 DG188			
I+ Positive Supply Current	1.5	3	0.8	mA	All V <sub>IN</sub> = 0 V	
I- Negative Supply Current	-5	-5.5	-3			
I <sub>L</sub> Logic Supply Current	4.5	4.5	3.2			
I <sub>R</sub> Reference Supply Current	-2	-2	-2			
I+ Positive Supply Current	1.5	0.1	0.8		All V <sub>IN</sub> = 5 V	
I- Negative Supply Current	-5	-4	-3			
I <sub>L</sub> Logic Supply Current	4.5	4.5	3.2			
I <sub>R</sub> Reference Supply Current	-2	-2	-2			

CMJA + NC – DG184,DG185  
CMJA + NIP – DG183

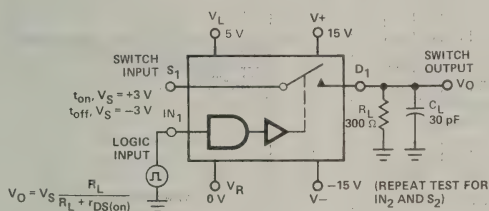
CMJB + NC – DG181, DG182,  
DG190, DG191  
CMJB + NIP – DG180, DG189

CMJC + NC – DG187, DG188  
CMJC + NIP – DG186

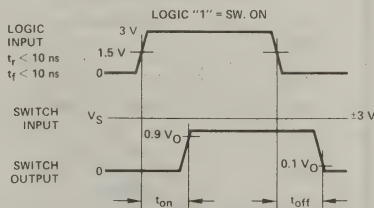
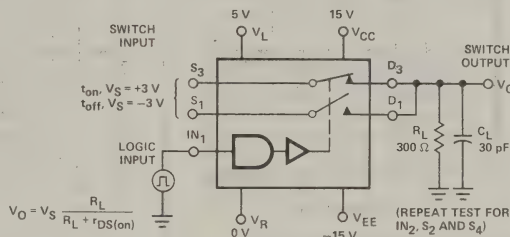
## SWITCHING TIME TEST CIRCUITS

Switch output waveform shown for V<sub>S</sub> = constant with logic input waveform as shown. Note that V<sub>S</sub> may be + or – as per switching time test circuit. V<sub>O</sub> is the steady state output with switch on. Feedthrough via gate capacitance may result in spikes at leading and trailing edge of output waveform.

DG180 – DG185



DG186 – DG191



NOTE: LOGIC INPUT WAVEFORM IS INVERTED FOR SWITCHES THAT HAVE THE OPPOSITE LOGIC SENSE CONTROL

## APPLICATION HINTS\*

Switch Family	V+ Positive Supply Voltage (V)	V- Negative Supply Voltage (V)	V <sub>L</sub> Logic Supply Voltage (V)	V <sub>R</sub> Reference Supply Voltage (V)	V <sub>IN</sub> Logic Input Voltage V <sub>INH</sub> Min/ V <sub>INL</sub> Max (V)	V <sub>S</sub> Analog Voltage Range (V)
10 Ω and 30 Ω	+15** +10	-15 -20	+5 +5	Gnd Gnd	2.0/0.8 2.0/0.8	-7.5 to +15 -12.5 to +10
	+12	-12	+5	Gnd	2.0/0.8	-4.5 to +12
75 Ω	+15** +10	-15 -20	+5 +5	Gnd Gnd	2.0/0.8 2.0/0.8	-10 to +15 -15 to +10
	+12	-12	+5	Gnd	2.0/0.8	-7 to +12

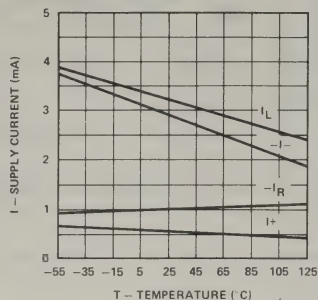
\*Application Hints are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

\*\*Electrical Parameter Chart based on V+ = +15 V, V- = -15 V, V<sub>L</sub> = 5 V, V<sub>R</sub> = Gnd.

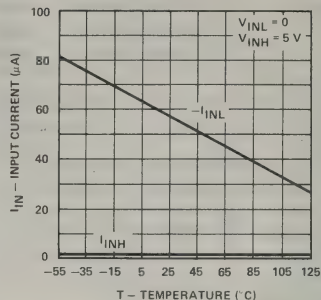


# TYPICAL CHARACTERISTICS

Supply Current vs Temperature



$I_{IN}$  vs  $V_{IN}$  and Temperature



10  $\Omega$

DG180  
DG183  
DG186  
DG189

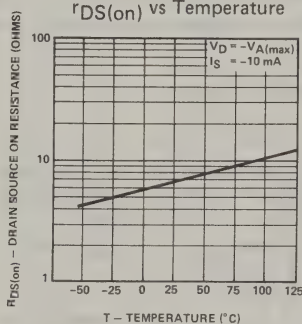
30  $\Omega$

DG181  
DG184  
DG187  
DG190

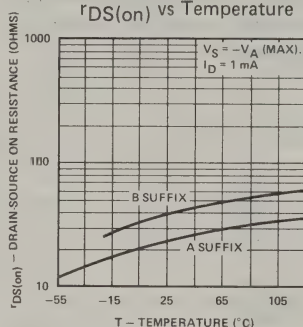
75  $\Omega$

DG182  
DG185  
DG188  
DG191

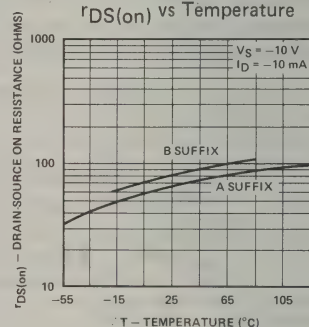
$r_{DS(on)}$  vs Temperature



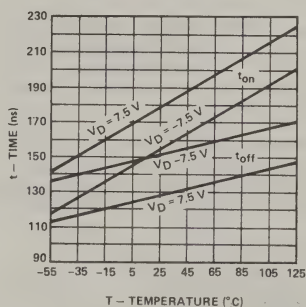
$r_{DS(on)}$  vs Temperature



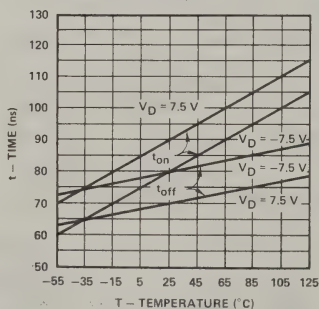
$r_{DS(on)}$  vs Temperature



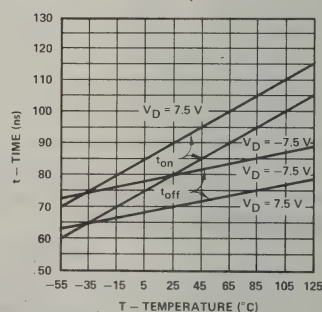
Switching Time vs  $V_D$  and Temperature



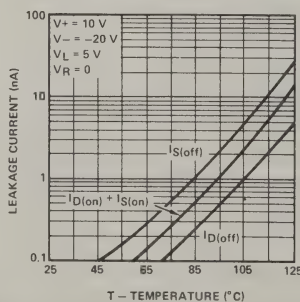
Switching Time vs  $V_D$  and Temperature



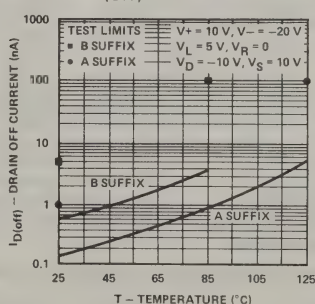
Switching Time vs  $V_D$  and Temperature



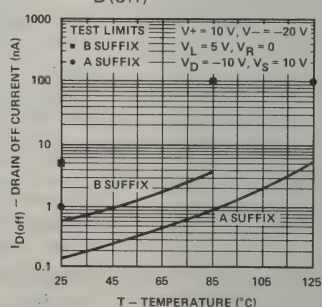
Leakage vs Temperature



$I_{D(off)}$  vs Temperature



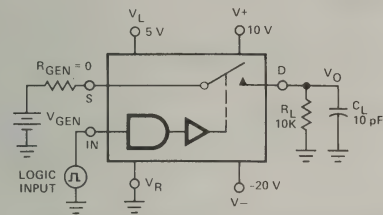
$I_{D(off)}$  vs Temperature





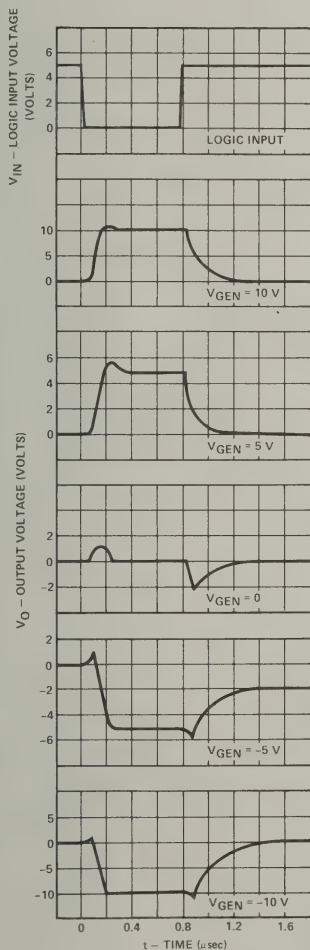
## TYPICAL CHARACTERISTICS (Cont'd)

Typical delay, rise, fall, settling times, and switching transients in this circuit.

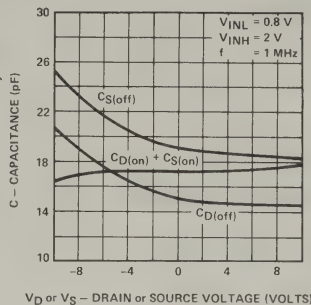


If  $R_{GEN}$ ,  $R_L$  or  $C_L$  is increased, there will be proportional increases in rise and/or fall times.

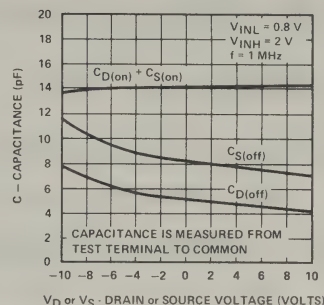
DG180, DG183, DG186  
DG189



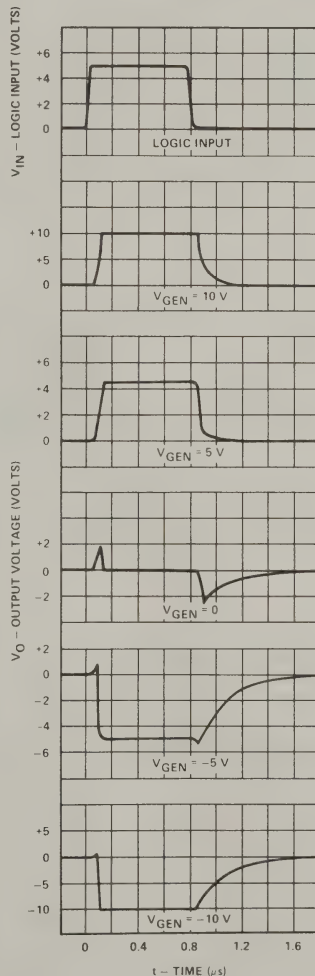
Capacitance vs  $V_D$  or  $V_S$   
10  $\Omega$  FET



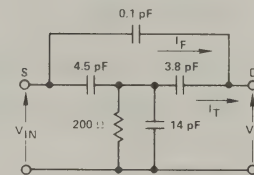
Capacitance vs  $V_D$  or  $V_S$   
30-75  $\Omega$  FET



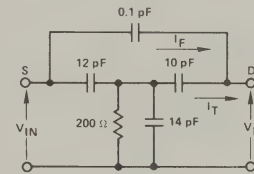
DG181, DG182, DG184,  
DG185, DG187, DG188,  
DG190, DG191



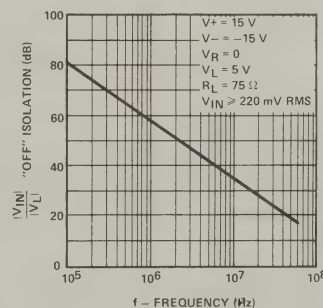
Equivalent "OFF" Circuit  
30-75  $\Omega$  FET



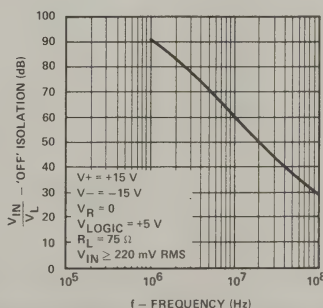
Equivalent "OFF" Circuit  
10  $\Omega$  FET



"OFF" Isolation vs Frequency  
10  $\Omega$  FET



"OFF" Isolation vs Frequency  
30-75  $\Omega$  FET



# Dual Monolithic SPST CMOS Analog Switch



*designed for . . .*

- **Low Transient Switching**  
i.e. Sample and Hold Circuits
- **Switching Multiple Signals**  
such as Multiplexing Inputs
- **TTL Compatible Switching**  
Systems
- **High Frequency Signal**  
Switching, such as Video Signals

## BENEFITS

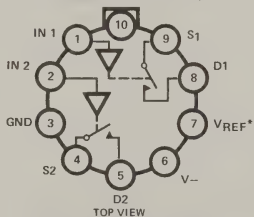
- **Environmentally Rugged**
  - Latch-proof CMOS
- **Easily Interfaced**
  - TTL, DTL and CMOS Direct Control Interface Over Military Temperature Range
- **Reduces External Component Requirements**
  - $\pm 15$  V Analog Signal Range with  $\pm 15$  V Supplies
- **Reduced System Cross-Talk**
  - Break-Before-Make Switching
- **Eliminates Signal Error**
  - 10 pA Typical Leakage From Source or Drain
  - Low Charge Coupling

## DESCRIPTION

The DG200 is a 2-channel, single-pole, single-throw analog switch which employs CMOS technology to insure low and nearly constant ON resistance over the entire analog signal range. The switch will conduct current in either direction with no offset voltage in the ON condition, and block voltages up to 30 V peak-to-peak in the OFF condition. The ON-OFF state of each switch is controlled by a driver. With a logic "0" at the input to the driver (0 V to 0.8 V) the switch will be ON, and a logic "1" (2.4 V to 15 V) will turn the switch OFF. The input can thus be directly interfaced with TTL, DTL, RTL, CMOS and certain PMOS circuits. Switch action is break-before-make. For new designs, use the DG200A.

## PIN CONFIGURATIONS

**Metal Can Package**  
V+ (SUBSTRATE AND CASE)



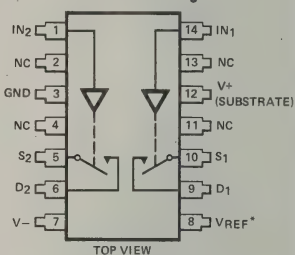
ORDER NUMBERS:  
DG200AA OR DG200BA  
SEE PACKAGE 2

LOGIC	SWITCH
0	ON
1	OFF

\*Optional (Normally Left Open)

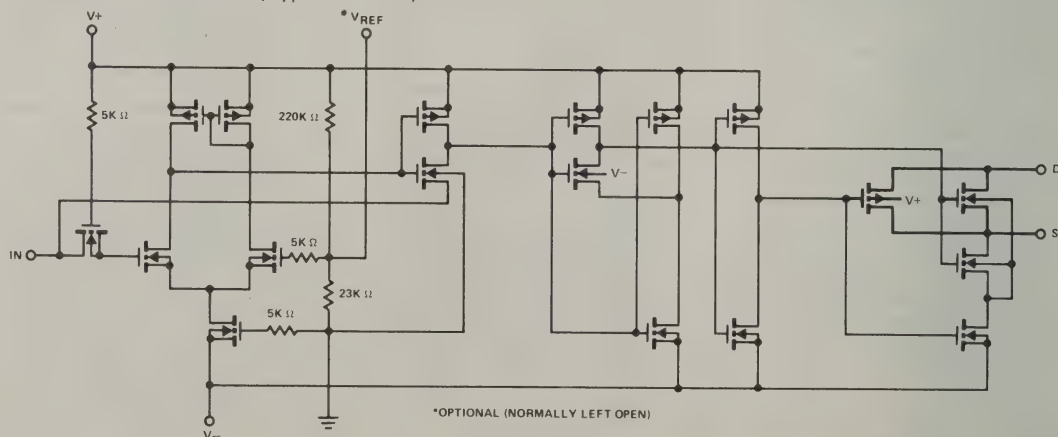
SWITCH STATES ARE FOR LOGIC "1" INPUT (POSITIVE LOGIC)

**Dual-In-Line Package**



ORDER NUMBERS:  
DG200AP OR DG200BP  
SEE PACKAGE 11  
DG200CJ  
SEE PACKAGE 7

## SCHEMATIC DIAGRAM (Typical Channel)



\*OPTIONAL (NORMALLY LEFT OPEN)

## ABSOLUTE MAXIMUM RATINGS

$V_{IN}$ and $V_{REF}$ to Ground	-0.3 V, $V_+$
$V_S$ or $V_D$ to $V_+$	0, -32 V
$V_S$ or $V_D$ to $V_-$	0, 32 V
$V_+$ to Ground	16 V
$V_-$ to Ground	-16 V
Current, Any Terminal Except S or D	30 mA
Current, S or D	20 mA
Current, S or D Pulsed	
(1 msec, 10% Duty Cycle Max)	100 mA
Operating Temp. (A Suffix)	-55 to 125°C
(B Suffix)	-20 to 85°C
(C Suffix)	0 to 70°C

Storage Temp. (A & B Suffix)	-65 to 150°C
(C Suffix)	-65 to +125°C
Power Dissipation (Package)*	
Metal Can**	450 mW
14 Pin DIP***	825 mW
14 Pin Plastic DIP****	470 mW

\*Device mounted with all leads welded or soldered to PC board.

\*\*Derate 6 mW/°C above 75°C

\*\*\*Derate 11 mW/°C above 75°C

\*\*\*\*Derate 6.5 mW/°C above 25°C

**ELECTRICAL CHARACTERISTICS** All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC			TYP† 25°C	MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V+ = 15 V, V− = −15 V, Gnd = 0, VREF = Open***											
				A SUFFIX			B/C SUFFIX															
				−55°C	25°C	125°C	−20/ 0°C	25°C	85/ 70°C													
1	SWITCH	VANALOG	Minimum Analog Signal Handling Capability	±15		±15	±15		±15	±15	V	Switch ON IS = 10 mA										
2		ID(on)	Drain Source ON Resistance	45	70	70	100	80	80	100	Ω	VD = 10 V VD = −10 V IS = −1 mA										
3			IS(off)	Source OFF Leakage Current	+0.01		2	100		5	100	nA	VS = 14 V, VD = −14 V VS = −14 V, VD = 14 V VD = 14 V, VS = −14 V VD = −14 V, VS = 14 V									
4				ID(off)	Drain OFF Leakage Current	−0.02		−2	−100		−5		−100	VIN = 2.4 V								
5					ID(on)	Channel ON Leakage Current	+0.1		2	100			5	100	VIN = 0.8 V							
6						ID(on)	Channel ON Leakage Current	−0.02		−2	−100			−5		−100	VD = VS = 14 V VD = VS = −14 V					
7							ID(on)	Channel ON Leakage Current	+0.1		2		200			−5		200	VIN = 2.4 V			
8								ID(on)	Channel ON Leakage Current	−0.1			−2	−200				−5		−200	VIN = 15 V	
9									ID(on)	Channel ON Leakage Current	0.0009			−1		−10				−1		−10
10	ID(on)	Channel ON Leakage Current								0.005			1	10				1		10		VIN = 0 V
11		ID(on)	Channel ON Leakage Current							−150										See Switching Time Test Circuit		
12			ID(on)	Channel ON Leakage Current						−0.0015		−1	−10			−1		−10				
13				ID(on)	Channel ON Leakage Current					440		1000		1000		See Switching Time Test Circuit						
14					ID(on)	Channel ON Leakage Current				370		500		500			See Switching Time Test Circuit					
15						ID(on)	Channel ON Leakage Current			9.0								See Switching Time Test Circuit				
16							ID(on)	Channel ON Leakage Current		9.0									See Switching Time Test Circuit			
17								ID(on)	Channel ON Leakage Current	25											See Switching Time Test Circuit	
18	ID(on)								Channel ON Leakage Current	72												See Switching Time Test Circuit
19		ID(on)							Channel ON Leakage Current	+2.3		4		4						See Switching Time Test Circuit		
20			ID(on)						Channel ON Leakage Current	−2.3		−4		−4								
21				ID(on)					Channel ON Leakage Current	+0.7		2		2		See Switching Time Test Circuit						
22					ID(on)				Channel ON Leakage Current	−0.6		−2		−2			See Switching Time Test Circuit					
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123		ID(on)							Channel ON Leakage Current											See Switching Time Test Circuit		
124			ID(on)						Channel ON Leakage Current													
125				ID(on)					Channel ON Leakage Current							See Switching Time Test Circuit						
126					ID(on)				Channel ON Leakage Current								See Switching Time Test Circuit					
127						ID(on)			Channel ON Leakage Current									See Switching Time Test Circuit				
128							ID(on)		Channel ON Leakage Current										See Switching Time Test Circuit			
129								ID(on)	Channel ON Leakage Current												See Switching Time Test Circuit	
130	ID(on)								Channel ON Leakage Current													See Switching Time Test Circuit
131		ID(on)							Channel ON Leakage Current											See Switching Time Test Circuit		
132			ID(on)						Channel ON Leakage Current													
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136							ID(on)		Channel ON Leakage Current										See Switching Time Test Circuit			
137								ID(on)	Channel ON Leakage Current												See Switching Time Test Circuit	
138	ID(on)								Channel ON Leakage Current													See Switching Time Test Circuit
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140			ID(on)						Channel ON Leakage Current													
141				ID(on)					Channel ON Leakage Current							See Switching Time Test Circuit						
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150					ID(on)				Channel ON Leakage Current								See Switching Time Test Circuit					
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152							ID(on)		Channel ON Leakage Current										See Switching Time Test Circuit			
153								ID(on)	Channel ON Leakage Current												See Switching Time Test Circuit	
154	ID(on)								Channel ON Leakage Current													See Switching Time Test Circuit
155		ID(on)							Channel ON Leakage Current											See Switching Time Test Circuit		
156			ID(on)						Channel ON Leakage Current													
157				ID(on)					Channel ON Leakage Current							See Switching Time Test Circuit						
158					ID(on)				Channel ON Leakage Current								See Switching Time Test Circuit					
159						ID(on)			Channel ON Leakage Current									See Switching Time Test Circuit				
160							ID(on)		Channel ON Leakage Current										See Switching Time Test Circuit			
161								ID(on)	Channel ON Leakage Current												See Switching Time Test Circuit	
162	ID(on)								Channel ON Leakage Current													See Switching Time Test Circuit
163		ID(on)							Channel ON Leakage Current											See Switching Time Test Circuit		
164			ID(on)						Channel ON Leakage Current													
165				ID(on)					Channel ON Leakage Current							See Switching Time Test Circuit						
166					ID(on)				Channel ON Leakage Current								See Switching Time Test Circuit					
167						ID(on)			Channel ON Leakage Current									See Switching Time Test Circuit				
168							ID(on)		Channel ON Leakage Current										See Switching Time Test Circuit			
169								ID(on)	Channel ON Leakage Current												See Switching Time Test Circuit	
170	ID(on)								Channel ON Leakage Current													See Switching Time Test Circuit
171		ID(on)							Channel ON Leakage Current											See Switching Time Test Circuit		
172			ID(on)						Channel ON Leakage Current													

### NOTES:

†Typical Values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

\* $I_{D(on)}$  is leakage from driver into "ON" switch.

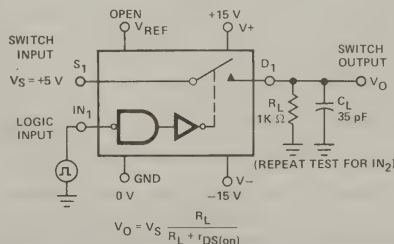
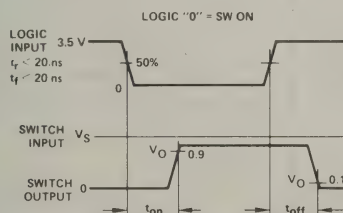
\*\*\*"OFF" isolation  $\Delta = 20 \log V_S/V_D$ ,  $V_S = \text{input to OFF switch}$ ,  $V_D = \text{output}$

\*\*\*Functional operation is possible for supply voltages less than 15 V, but the input logic threshold will shift. For  $V_+ = -V_- = 10\text{ V}$ , 1.4 V may be applied to  $V_{REF}$  terminal. The  $V_{REF}$  terminal has  $R_{IN} \approx 21\text{ K } \Omega$ . See Applications Section.

ICXE

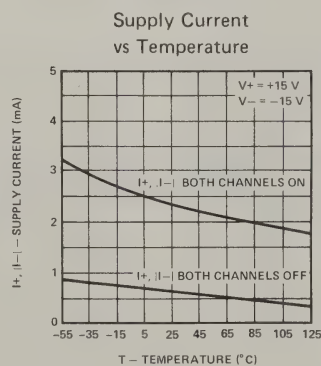
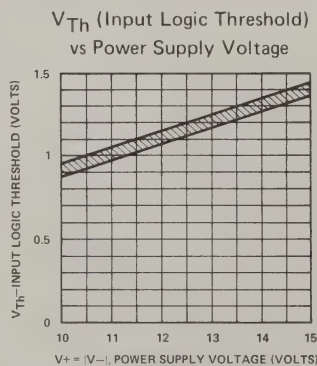
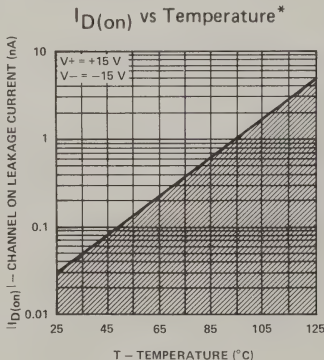
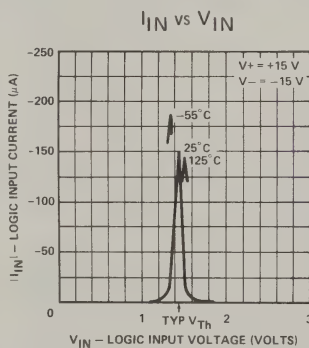
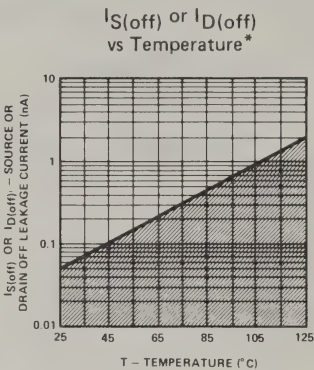
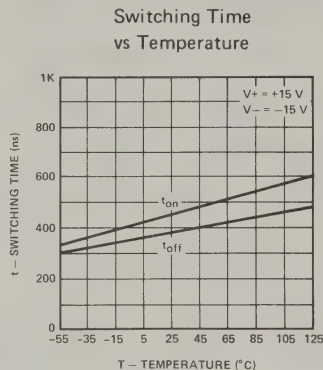
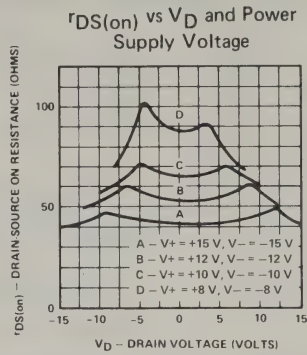
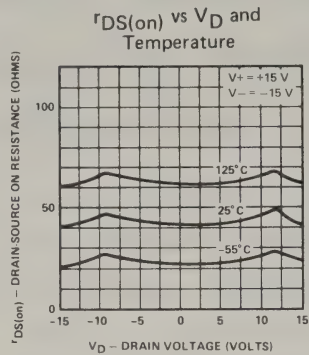
## SWITCHING TIME TEST CIRCUIT

Switch output waveform shown for  $V_S = \text{constant}$  with logic input waveform as shown. Note that  $V_S$  may be + or - as per switching time test circuit.  $V_O$  is the steady state output with switch on. Feedthrough via gate capacitance may result in spikes at leading and trailing edge of output waveform.

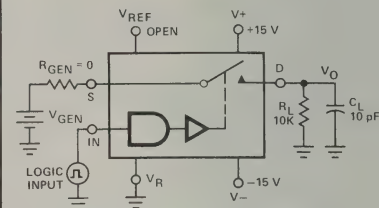




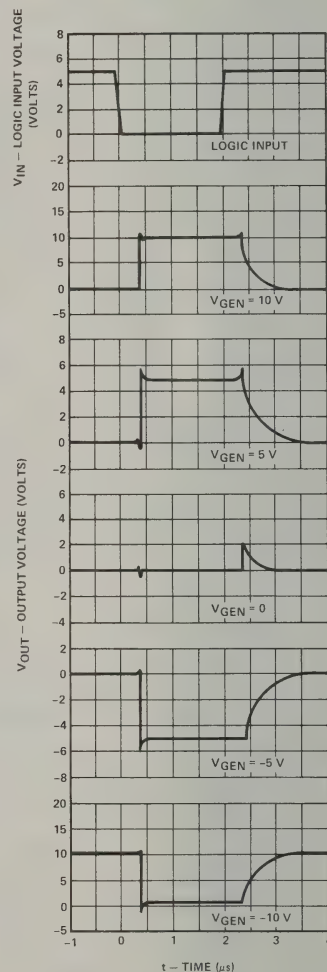
# TYPICAL CHARACTERISTICS



Typical delay, rise, fall, settling times, and switching transients in this circuit.



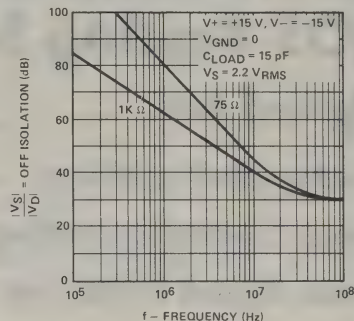
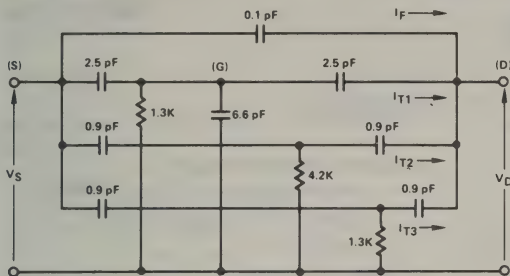
If  $R_{GEN}$ ,  $R_L$  or  $C_L$  is increased, there will be proportional increases in rise and/or fall RC times. Applying  $V_{GEN}$  to D rather than S results in much greater spikes.



\*The net leakage into the source or drain is the n-channel leakage minus the p-channel leakage. This difference can be positive, negative, or zero depending on the analog voltage and temperature, and will vary greatly from unit to unit.



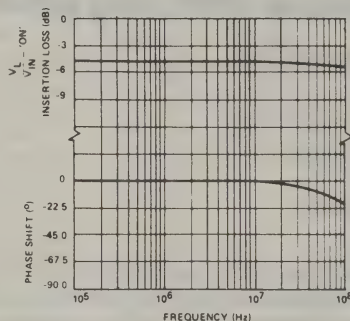
## "OFF" Isolation Equivalent Circuit and Data



## APPLICATIONS

### Application Hints\*

V+	V-	VREF	VIN	VS or
Positive	Negative	Reference	Logic Input	VD
Supply	Supply	Pin	Voltage	Analog
Voltage	Voltage	Connection	VINH Min/ VINL Max	Voltage
(V)	(V)	(V)	(V)	Range
(V)	(V)	(V)	(V)	(V)
+15**	-15	Open	2.4/0.8	-15 to +15
+12	-12	Open or 1.4 V	2.4/0.8	-12 to +12
+10	-10	1.4 V	2.4/0.8	-10 to +10
+8***	-8	1.4 V	2.4/0.8	-8 to +8



\*Application Hints are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

\*\*Electrical Characteristics chart based on V+ = +15 V, V- = -15 V, VREF = Open.

\*\*\*Operation below ±8 V is not recommended.

## Logic Inputs

Logic input circuitry protects the input MOS gate from static transients. A series MOS device shuts off when VIN exceeds the positive power supply. Negative transients are clamped to ground by a diode clamp.

The input voltage characteristics have a current spike occurring at the transition voltage when the logic goes from VINH to VINL. If a series resistor is used for additional static protection, it should be limited to less than 4.7 KΩ to insure switching with worst case current spikes.

## The Function of VREF

VREF is an internal connection which allows the user to establish the logic threshold voltage at which the switch changes state. The actual threshold voltage is equal to the voltage on the VREF pin. VREF is internally connected for a 1.4 V threshold at V+ = +15 V. For other thresholds and/or supply voltages, one may connect VREF to a voltage source or resistive divider whose output voltage is equal to the desired threshold. The internal impedance of VREF is 21 KΩ ±30%.

Additionally, to adjust VREF, a single pullup resistor can be used from the VREF pin to a positive supply voltage to shunt the upper internal divider resistor. The equation below shows the calculation of the shunt resistor for the desired logic threshold voltage — this calculation is based on nominal internal resistor values, which are ±30% in absolute magnitude. The adjusted trip point voltage (VREF) should be limited to an upper level of 5 V to avoid input logic switching transition hysteresis.

$$R_{SHUNT} = \frac{R1 \times R2 \left( \frac{V^+}{V_{tr}} - 1 \right)}{R1 - R2 \left( \frac{V^+}{V_{tr}} - 1 \right)}$$

Calculation of RSHUNT

Where R1 ≈ 220 KΩ: nominal values,  
R2 ≈ 23 KΩ ±30% run to run

Example: for V+ = 15 V, VTRIP = 5 V, using nominal R1, R2 calc RSHUNT = 58 KΩ.

# Dual Monolithic SPST CMOS Analog Switch

***designed for . . .***

- **Analog Multiplexing**
- **Servo Control Switching**
- **Video Signal Switching**
- **Remove Switching under TTL Logic Control**

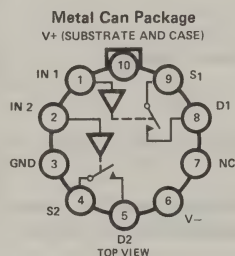
## BENEFITS

- **Environmentally Rugged**
  - 44V Power Supply Maximum Rating
  - Static Protected Logic Inputs
  - Latchproof
- **Easily Interfaced**
  - TTL and CMOS Compatible without Pull-Up Resistors
- **Pin for Pin Compatible with**
  - Analog Devices ADG200
  - Harris HI200
  - Intersil DG200
  - Siliconix DG200

### DESCRIPTION

The DG200A designed on the Siliconix PLUS-40 CMOS process provides solid state switch action with 70 ohms contact (ON) resistance and very high OFF resistance. True switch action takes place over the full analog signal range of  $\pm 15$  V, with Break-Before-Make operation to prevent momentary shorting of signal inputs.

## PIN CONFIGURATIONS

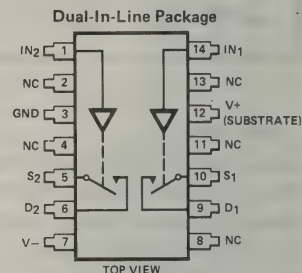


LOGIC	SWITCH
0	ON
1	OFF

ORDER NUMBERS:  
DG200AAA OR DG200ABA  
SEE PACKAGE 2

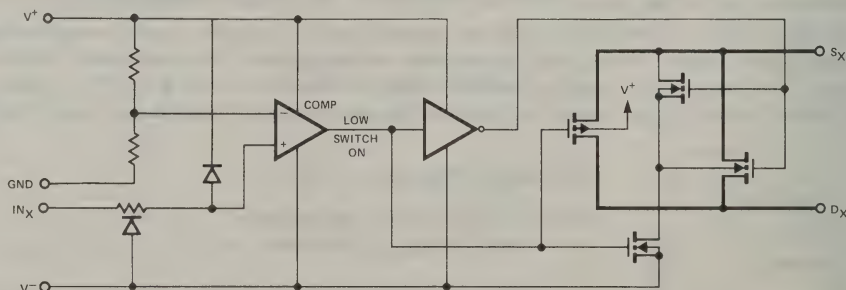
**ORDER NUMBERS:  
DG200AAK OR DG200ABK  
OR DG200ACK  
SEE PACKAGE 9**

DG200ACJ  
SEE PACKAGE 7



SWITCH STATES ARE FOR LOGIC "1" INPUT (POSITIVE LOGIC)

### SCHEMATIC DIAGRAM (typical channel)



# ABSOLUTE MAXIMUM RATINGS

Voltages referenced to V-

V+	44 V
GND.	25 V
Digital inputs <sup>4</sup> , V <sub>S</sub> , V <sub>D</sub>	-2 V to (V <sup>+</sup> +2 V) or 20 mA, whichever occurs first.
Current, Any Terminal Except S or D	30 mA
Current, S or D	20 mA
Current, S or D Pulsed (1 msec, 10% Duty Cycle Max)	100 mA
Operating Temp. (A Suffix)	-55 to 125°C
(B Suffix)	-20 to 85°C
(C Suffix)	0 to 70°C

Storage Temp. (A & B Suffix)	-65 to 150°C
(C Suffix)	-65 to +125°C
Power Dissipation (Package)*	
Metal Can**	450 mW
14 Pin DIP***	825 mW
14 Pin Plastic DIP****	470 mW

\*Device mounted with all leads welded or soldered to PC board.

\*\* Derate 6 mW/°C above 75°C

\*\*\* Derate 11 mW/°C above 75°C

\*\*\*\* Derate 6.5 mW/°C above 25°C

**ELECTRICAL CHARACTERISTICS** All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC			TYP <sup>1</sup> 25°C	MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V <sup>+</sup> = 15 V, V <sup>-</sup> = -15 V, Gnd = 0,		
				A SUFFIX			B/C SUFFIX						
				-55°C	25°C	125°C	-20/ 0°C	25°C	85/ 70°C				
1	SWITCH	V <sub>ANALOG</sub>	Minimum Analog Signal Handling Capability	±15		±15	±15		±15	±15	V		
2		r <sub>DS(on)</sub>	Drain Source ON Resistance	45	70	70	100	80	80	100	Ω	V <sub>D</sub> = 10 V	V <sub>IN</sub> = 0.8 V
3				45	70	70	100	80	80	100		V <sub>D</sub> = -10 V	I <sub>S</sub> = -1 mA
4		I <sub>S(off)</sub>	Source OFF Leakage Current	+0.01		2	100		5	100	nA	V <sub>S</sub> = +14 V, V <sub>D</sub> = -14 V	V <sub>IN</sub> = 2.4 V
5				-0.02		-2	-100		-5	-100		V <sub>S</sub> = -14 V, V <sub>D</sub> = 14 V	
6		I <sub>D(off)</sub>	Drain OFF Leakage Current	+0.01		2	100		5	100		V <sub>D</sub> = 14 V, V <sub>S</sub> = -14 V	
7				-0.02		-2	-100		-5	-100		V <sub>D</sub> = -14 V, V <sub>S</sub> = 14 V	
8		I <sub>D(on)</sub> <sup>2</sup>	Channel ON Leakage Current	+0.1		2	200		-5	200	μA	V <sub>D</sub> = V <sub>S</sub> = 14 V	V <sub>IN</sub> = 0.8 V
9				-0.1		-2	-200		-5	-200		V <sub>D</sub> = V <sub>S</sub> = -14 V	
10	INPUT	I <sub>INH</sub>	Input Current	0.0009		-1	-10		-1	-10	μA	V <sub>IN</sub> = 2.4 V	
11		I <sub>INL</sub>	Input Voltage High	0.005		1	10		1	10		V <sub>IN</sub> = 15 V	
12		I <sub>INL</sub>	Input Current Input Voltage Low	-0.0015		-1	-10		-1	-10		V <sub>IN</sub> = 0 V	
13	DYNAMIC	t <sub>on</sub>	Turn-ON Time	440		1000		1000		ns	See Switching Time Test Circuit		
14		t <sub>off</sub>	Turn-OFF Time	370		500		500					
15		Q	Charge Injection	-10						pC	C <sub>L</sub> = 1000pF, V <sub>GEN</sub> = 0V, R <sub>GEN</sub> = 0Ω		
16		C <sub>S(off)</sub>	Source OFF Capacitance	9.0						pF	V <sub>S</sub> = 0, V <sub>IN</sub> = 5 V	f = 140 kHz	
17			C <sub>D(off)</sub>	Drain OFF Capacitance	9.0						V <sub>D</sub> = 0, V <sub>IN</sub> = 5V		
18		C <sub>D(on)</sub> + C <sub>S(on)</sub>	Channel ON Capacitance	25							V <sub>D</sub> = V <sub>S</sub> = 0, V <sub>IN</sub> = 0		
19		OIRR <sup>3</sup>	OFF Isolation	75						dB	V <sub>IN</sub> = 5 V		
20		CCRR	Channel to Channel Crosstalk	90							V <sub>S</sub> = 2 V <sub>pp</sub> Z <sub>L</sub> = 75Ω f = 1 MHz		
21	SUP	I <sup>+</sup>	Positive Supply Current	0.8		2		2	mA	Both Channels "ON", or "OFF" V <sub>IN</sub> = 0 or 2.4 V			
22		I <sup>-</sup>	Negative Supply Current	-23		-1		-1					

## NOTES:

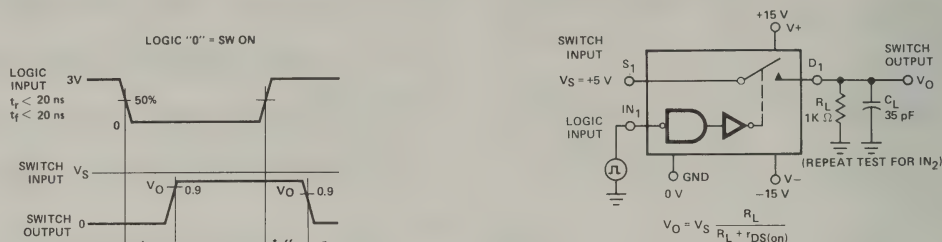
- Typical Values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.
- I<sub>D(on)</sub> is leakage from driver into "ON" switch.
- "OFF" isolation is 20 log V<sub>S</sub>/V<sub>D</sub>. V<sub>S</sub> = input to OFF switch, V<sub>D</sub> = output
- Signals on S<sub>X</sub>, D<sub>X</sub> or I<sub>NX</sub> exceeding V<sup>+</sup> or V<sup>-</sup> will be clamped by internal diodes. Limit forward diode current to maximum current ratings.

ICME

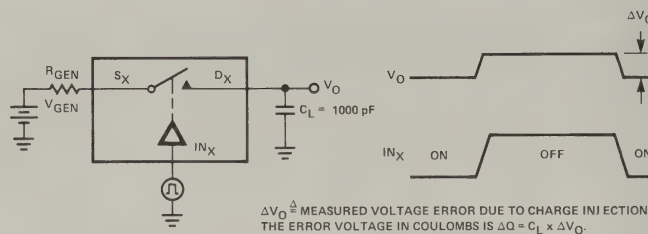


### SWITCHING TIME TEST CIRCUIT

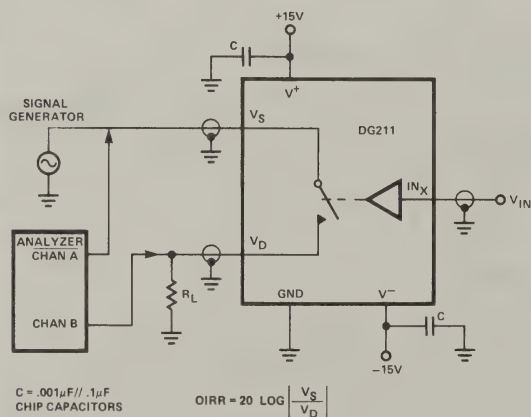
Switch output waveform shown for  $V_S = \text{constant}$  with logic input waveform as shown. Note that  $V_S$  may be + or - as per switching time test circuit.  $V_O$  is the steady state output with switch on. Feedthrough via gate capacitance may result in spikes at leading and trailing edge of output waveform.



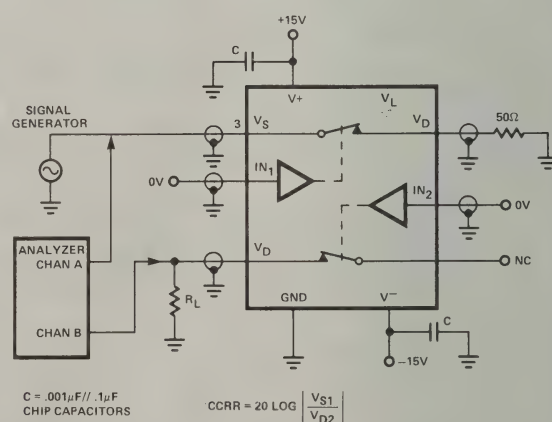
### CHARGE INJECTION TEST CIRCUIT



### OIRR OFF ISOLATION TEST CIRCUIT



### CCRR CHANNEL TO CHANNEL CROSSTALK TEST CIRCUIT





# Quad Monolithic SPST CMOS Analog Switch *designed for . . .*



DG201

- **Low Transient Switching**  
i.e. Sample and Hold Circuits
- **Switching Multiple Signals**  
such as Multiplexing Inputs
- **High Frequency Signal**  
Switching
- **TTL Compatible Systems**

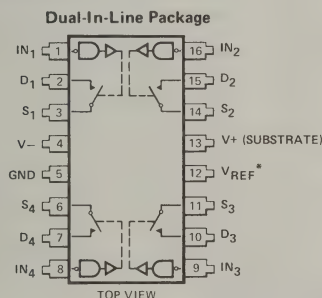
## BENEFITS

- **Environmentally Rugged**
  - Latch-proof CMOS
- **Reduced Switching Error**
  - Low Charge Coupling
- **Easily Interfaced**
  - TTL, DTL and CMOS Direct Control Interface Over Military Temperature Range
- **Reduces External Component Requirements**
  - $\pm 15$  V Analog Signal Range with  $\pm 15$  V Supplies
- **Reduced System Cross-Talk**
  - Break-Before-Make Switching
- **Eliminates Signal Error**
  - 10 pA Typical Leakage From Source or Drain

## DESCRIPTION

The DG201 is a 4-channel single pole signal throw analog switch which employs CMOS technology to insure low and nearly constant ON resistance over the entire analog signal range. The switch will conduct current in either direction with no offset voltage in the ON condition, and block voltages up to 30 V peak-to-peak in the OFF condition. The ON-OFF state of each switch is controlled by a driver. With a logic "0" at the input to the driver (0 V to 0.8 V) the switch will be ON, and a logic "1" (2.4 V to 15 V) will turn the switch OFF. The input can thus be directly interfaced with TTL, DTL, RTL, CMOS and certain PMOS circuits. Switch action is break-before-make. For new designs, use the DG201A.

## PIN CONFIGURATION



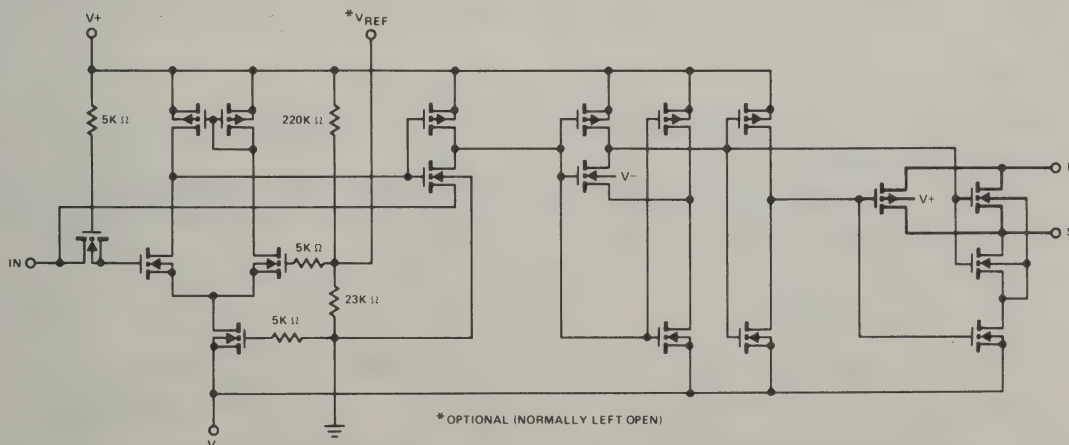
ORDER NUMBERS:  
DG201AP OR DG201BP  
SEE PACKAGE 12

DG201CJ  
SEE PACKAGE 8

LOGIC	SWITCH
0	ON
1	OFF

\*Optional (Normally Left Open)  
SWITCH OPEN FOR LOGIC "1" INPUT (POSITIVE LOGIC)

## SCHEMATIC DIAGRAM (Typical Channel)



3

Analog Switches

# ABSOLUTE MAXIMUM RATINGS

$V_{IN}$ and $V_{REF}$ to Ground	-0.3 V, V+
$V_S$ or $V_D$ to V+	0, -32 V
$V_S$ or $V_D$ to V-	0, 32 V
V+ to Ground	16 V
V- to Ground	-16 V
Current, Any Terminal Except S or D	30 mA
Continuous Current, S or D	20 mA
Peak Current, S or D	
(pulsed at 1 msec, 10% duty cycle max)	70 mA
Storage Temperature (A & B Suffix)	-65 to 150°C
(C Suffix)	-65 to 125°C

Operating Temperature (A Suffix)	-55 to 125°C
(B Suffix)	-20 to 85°C
(C Suffix)	0 to 70°C

Power Dissipation (Package)\*

16 Pin DIP**	900 mW
16 Pin Plastic DIP***	470 mW

\*Device mounted with all leads soldered or welded to PC board.

\*\*Derate 12 mW/°C above 75°C

\*\*\*Derate 6.5 mW/°C above 25°C

**ELECTRICAL CHARACTERISTICS** All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC			TYP† 25°C	MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V+ = 15 V, V- = -15 V, Gnd = 0, VREF = Open***		
				A SUFFIX			B/C SUFFIX						
				-55°C	25°C	125°C	-20°C/C/ 0°C	25°C	85°C/ 70°C				
1	VANALOG	Minimum Analog Signal Handling Capability	±15		±15	±15		±15	±15	V	Switch ON IS = 10 mA		
2	SWITCHING	rDS(on)	Drain-Source ON Resistance	115	175	175	250	200	200	250	Ω	VD = 10 V	VIN = 0.8 V, IS = -1 mA
3				75	175	175	250	200	200	250		VD = -10 V	
4		IS(off)	Source OFF Leakage Current	0.01		1	100		5	100	nA	VS = 14 V, VD = -14V	VIN = 2.4 V
5				-0.02		-1	-100		-5	-100		VS = -14V, VD = 14V	
6		ID(off)	Drain OFF Leakage Current	0.01		1	100		5	100		VD = 14 V, VS = -14V	
7			-0.02		-1	-100		-5	-100	VD = -14V, VS = 14V			
8	INPUT	ID(on)*	Drain ON Leakage Current	0.1		1	200		5	200		VD = VS = 14V	
9				-0.15		-1	-200		-5	-200	VD = VS = -14V		
10		IINH	Input Current, Input Voltage High	-0.004		-1	-10		-1	-10	VIN = 2.4 V		
11				.003		1	10		1	10	VIN = 15 V		
12			IIN(peak)	Peak Input Current Required for Transition	-120						μA	See Curve IIN vs VIN	
13		IINL	Input Current, Input Voltage Low	-0.004		-1	-10		-1	-10		VIN = 0	
14		ton	Turn-ON Time	580		1000					ns	See Switching Time Test Circuit	
15		toff	Turn-OFF Time	370		500							
16	DYNAMIC	CS(off)	Source OFF Capacitance	7							pF	VS = 0, VIN = 5 V	f = 140 KHz
17				Drain OFF Capacitance	7							VD = 0, VIN = 5 V	
18			CD(on) + CS(on)	Channel ON Capacitance	20							VD = VS = 0, VIN = 0	
19			Off Isolation**	54							dB	VIN = 5 V, RL = 1K Ω, CL = 20 pF VS = 7 VRMS, f = 500 kHz	
20	SUPPLY	I+	Positive Supply Current	2.1		4.0			4.0	mA	One Channel "ON," VIN = 0		
21		I-	Negative Supply Current	-2.1		-4.0			-4.0				
22		I+ Standby	Positive Supply Current	1.4		3.0			3.0		All Channels "OFF," VIN = 5 V		
23		I- Standby	Negative Supply Current	-1.4		-3.0			-3.0				

†Typical Values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

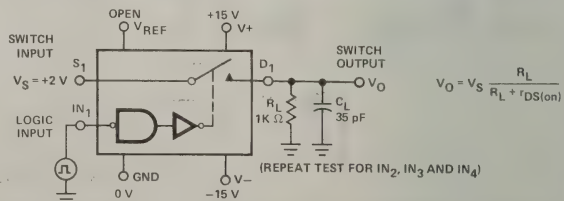
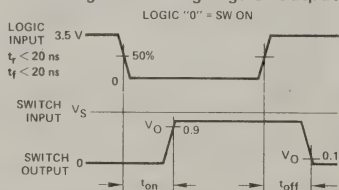
ICXF

\*I<sub>D(on)</sub> is leakage from driver into "ON" switch. \*\*\*"OFF" Isolation = 20 log  $\frac{|V_S|}{|V_D|}$

\*\*Functional operation is possible for supply voltages less than 15 V, but the input logic threshold will shift. For V+ = |V-| = 10 V, ±1.4 V may be applied to the V<sub>REF</sub> terminal. The V<sub>REF</sub> terminal has R<sub>IN</sub> ≈ 21K Ω. See the Applications Section.

## SWITCHING TIME TEST CIRCUIT

Switch output waveform shown for V<sub>S</sub> = constant with logic input waveform as shown. Note that V<sub>S</sub> may be + or - as per switching time test circuit. V<sub>O</sub> is the steady state output with switch on. Feedthrough via gate capacitance may result in spikes at leading and trailing edge of output waveform.



\*Application Hints are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

\*\*Electrical Characteristics chart based on  $V_+ = +15\text{ V}$ ,  $V_- = -15\text{ V}$ ,  $V_{REF} = \text{Open}$ .

\*\*\*Operation below  $\pm 8\text{ V}$  is not recommended.

V+ Positive Supply Voltage (V)	V- Negative Supply Voltage (V)	V <sub>REF</sub> Reference Pin Connection (V)	V <sub>IN</sub> Logic Input Voltage V <sub>INH</sub> Min/ V <sub>INL</sub> Max (V)	V <sub>S</sub> or V <sub>D</sub> Analog Voltage Range (V)
+15**	-15	Open	2.4/0.8	-15 to +15
+12	-12	Open or 1.4 V	2.4/0.8	-12 to +12
+10	-10	1.4 V	2.4/0.8	-10 to +10
+8***	-8	1.4 V	2.4/0.8	-8 to +8

### Logic Inputs

Logic input circuitry protects the input MOS gate from static transients. A series MOS device shuts off when  $V_{IN}$  exceeds the positive power supply. Negative transients are clamped to ground by a diode clamp.

The input voltage characteristics have a current spike occurring at the transition voltage when the logic goes from  $V_{INH}$  to  $V_{INL}$ . If a series resistor is used for additional static protection, it should be limited to less than  $5.6\text{ K}\Omega$  to insure switching with worst case current spikes.

### The Function of V<sub>REF</sub>

$V_{REF}$  is an internal connection which allows the user to establish the logic threshold voltage at which the switch changes state. The actual threshold voltage is equal to the voltage on the  $V_{REF}$  pin.  $V_{REF}$  is internally connected for a  $1.4\text{ V}$  threshold at  $V_+ = +15\text{ V}$ . For other thresholds and/or supply voltages, one may connect  $V_{REF}$  to a voltage source or resistive divider whose output voltage is equal to the desired threshold. The internal impedance of  $V_{REF}$  is  $21\text{ K}\Omega \pm 30\%$ .

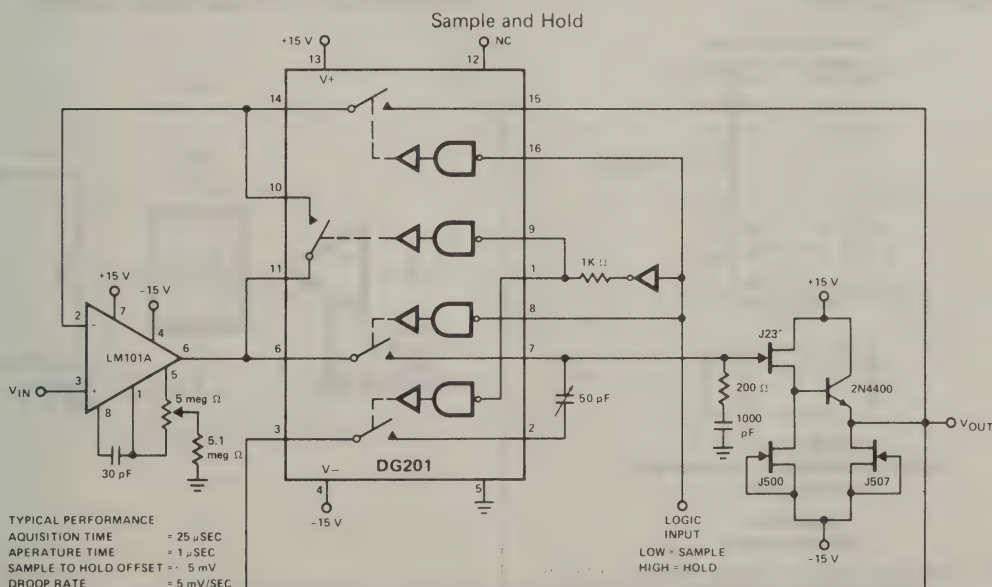
Additionally, to adjust  $V_{REF}$ , a single pullup resistor can be used from the  $V_{REF}$  pin to a positive supply voltage to shunt the upper internal divider resistor. The equation below shows the calculation of the shunt resistor for the desired logic threshold voltage — this calculation is based on nominal internal resistor values, which are  $\pm 30\%$  in absolute magnitude. The adjusted trip point voltage ( $V_{REF}$ ) should be limited to an upper level of  $5\text{ V}$  to avoid input logic switching transition hysteresis.

$$R_{SHUNT} = \frac{R1 \times R2 \left( \frac{V_+}{V_{tr}} - 1 \right)}{\left[ R1 - R2 \left( \frac{V_+}{V_{tr}} - 1 \right) \right]}$$

Calculation of R<sub>SHUNT</sub>

Where  $R1 \approx 220\text{ K}\Omega$  nominal values,  
 $R2 \approx 23\text{ K}\Omega$   $\pm 30\%$  run to run

Example: for  $V_+ = 15\text{ V}$ ,  $V_{TRIP} = 5\text{ V}$ , using nominal  $R1$ ,  $R2$  calc  $R_{SHUNT} = 58\text{ K}\Omega$ .



TYPICAL PERFORMANCE  
 ACQUISITION TIME =  $25\text{ }\mu\text{SEC}$   
 APERTURE TIME =  $1\text{ }\mu\text{SEC}$   
 SAMPLE TO HOLD OFFSET =  $5\text{ mV}$   
 DROOP RATE =  $5\text{ mV/SEC}$



# Quad Monolithic SPST CMOS Analog Switch designed for . . .

- Analog Multiplexing
- Remote Switching under TTL Logic Control
- Servo Control Switching
- Sampled Data Systems
- Programmable Gain Amplifiers

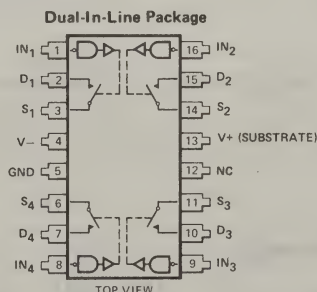
## BENEFITS

- **Environmentally Rugged**
  - 44V Power Supply Maximum Rating
  - Static Protected Logic Inputs
  - Latchproof
- **Easily Interfaced**
  - TTL and CMOS Compatible without Pull-Up Resistors
  - Logic Inputs Accept  $\pm$  Comparator Transitions without Series Current Limiting Resistors
- **Pin for Pin Compatible with**
  - Analog Devices ADG201
  - Harris HI201
  - Intersil DG201
  - Siliconix DG201

## DESCRIPTION

The DG201A designed on the Siliconix PLUS-40 CMOS process provides solid state switch action with 175 ohms contact resistance and very high OFF resistance. True switch action takes place over the full analog signal range of  $\pm 15V$ , with Break-Before-Make operation to prevent momentary shorting of signal inputs. Charge injection has been reduced by design to minimize spikes during switching transitions.

## PIN CONFIGURATION



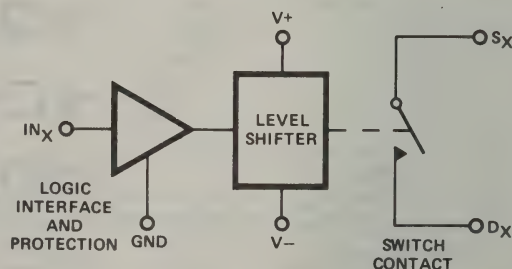
LOGIC	SWITCH
0	ON
1	OFF

ORDER NUMBERS:  
DG201AAK, DG201ABK OR DG201ACK  
SEE PACKAGE 10

DG201ACJ  
SEE PACKAGE 8

SWITCH OPEN FOR LOGIC "1" INPUT (POSITIVE LOGIC)

## FUNCTIONAL DIAGRAM (typical channel)





## ABSOLUTE MAXIMUM RATINGS

Voltages referenced to V-

V+ ..... 44 V

GND. .... 25 V

Digital inputs<sup>3</sup> V<sub>S</sub>, V<sub>D</sub>. .... -2 V to (V<sup>+</sup> +2 V) or  
20 mA, whichever occurs first.

Current, Any Terminal Except S or D ..... 30 mA

Continuous Current, S or D ..... 20 mA

Peak Current, S or D

(pulsed at 1 msec, 10% duty cycle max) ..... 70 mA

Storage Temperature (A &amp; B Suffix) ..... -65 to 150°C

(C Suffix) ..... -65 to 125°C

Operating Temperature (A Suffix) ..... -55 to 125°C

(B Suffix) ..... -20 to 85°C

(C Suffix) ..... 0 to 70°C

Power Dissipation (Package)\*

16 Pin DIP\*\* ..... 900 mW

16 Pin Plastic DIP\*\*\* ..... 470 mW

\*Device mounted with all leads soldered or welded  
to PC board.

\*\* Derate 12 mW/°C above 75°C

\*\*\* Derate 6.5 mW/°C above 25°C

**ELECTRICAL CHARACTERISTICS** All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC			TYP 25°	MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V+ = 15 V, V- = -15 V, Gnd = 0		
				A SUFFIX			B/C SUFFIX						
				-55°C	25°C	125°C	-20°C/ 0°C	25°C	85°C/ 70°C				
1	VANALOG	Minimum Analog Signal Handling Capability	±15		±15	±15		±15	±15	V			
2	SWITCH	IDS(on)	Drain Source ON Resistance	105	175	175	250	200	200	250	Ω	VD = 10 V	VIN = 0.8 V, IS = -1 mA
3				115	175	175	250	200	200	250		VD = -10 V	
4		IS(off)	Source OFF Leakage Current	0.01		1	100		5	100	nA	VS = 14 V, VD = -14 V	VIN = 2.4 V
5				-0.02		-1	-100		-5	-100		VS = -14 V, VD = 14 V	
6		ID(off)	Drain OFF Leakage Current	0.01		1	100		5	100		VD = 14 V, VS = -14 V	
7				-0.02		-1	-100		-5	-100		VD = -14 V, VS = 14 V	
8		ID(on)2	Drain ON Leakage Current	0.1		1	200		5	200	μA	VD = VS = 14 V	VIN = 0.8 V
9				-0.15		-1	-200		-5	-200		VD = VS = -14 V	
10	INPUT	Input Current	-0.004		-1	-10		-1	-10	VIN = 2.4 V			
11		IINH	Input Voltage High	.003		1	10		1	10		VIN = 15 V	
12		IINL	Input Current Input Voltage Low	-0.004		-1	-10		-1	-10	VIN = 0 V		
13	DYNAMIC	ton	Turn-ON Time	480		600		600		ns	See Switching Time Test Circuit		
14		t <sub>off</sub>	Turn-OFF Time	370		450		450					
15		Q	Charge Injection	20							pC	CL = 1000pF VGEN = 0V RGEN = 0Ω	
16	DYNAMIC	CS(off)	Source OFF Capacitance	5						pF	VS = 0, VIN = 5 V	f = 140 kHz	
17		CD(off)	Drain OFF Capacitance	5							VD = 0, VIN = 5V		
18		CD(on) + CS(on)	Channel ON Capacitance	16							VD = VS = 0, VIN = 0		
19	DYNAMIC	OIRR	OFF Isolation	70						dB	VIN = 5 V		
20		CCRR	Channel to Channel Crosstalk	90							VS = 2 Vpp, f = 100 KHz ZL = 75Ω		
21	SUP	I+	Positive Supply Current	.9		2		2		mA	All Channels "ON" or "OFF", VIN = 0 or 2.4 V		
22		I-	Negative Supply Current	-.3		-1		-1					

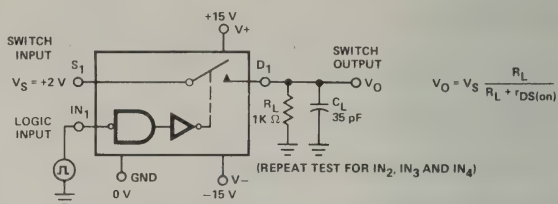
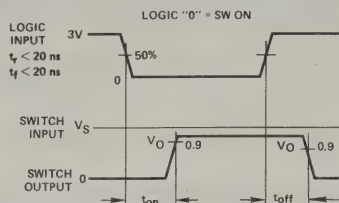
## NOTES:

ICMC-B

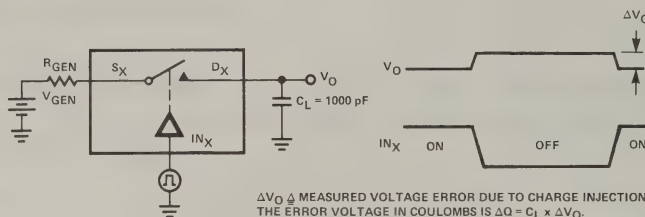
- Typical Values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.
- I<sub>D(on)</sub> is leakage from driver into "ON" switch.
- Signals on S<sub>X</sub>, D<sub>X</sub> or I<sub>NX</sub> exceeding V<sup>+</sup> or V<sup>-</sup> will be clamped by internal diodes. Limit forward diode current to maximum current ratings.

# SWITCHING TIME TEST CIRCUIT

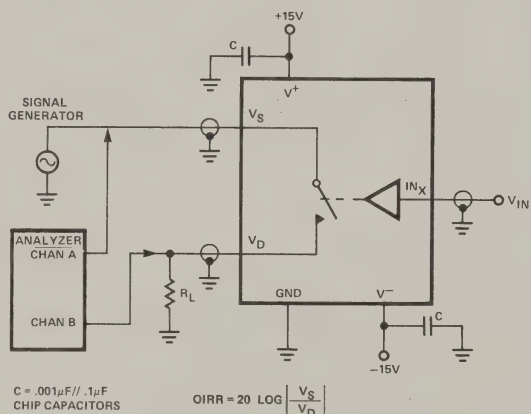
Switch output waveform shown for  $V_S$  = constant with logic input waveform as shown. Note that  $V_S$  may be + or - as per switching time test circuit.  $V_O$  is the steady state output with switch on. Feedthrough via gate capacitance may result in spikes at leading and trailing edge of output waveform.



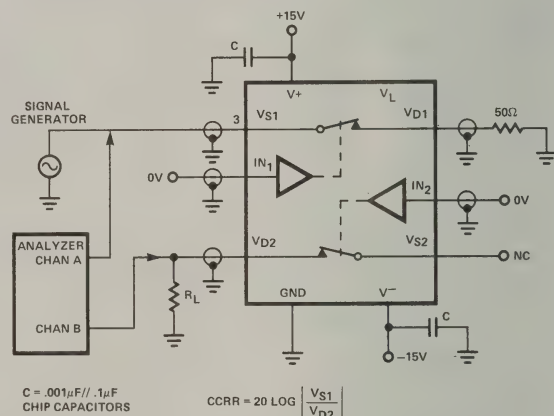
# CHARGE INJECTION TEST CIRCUIT



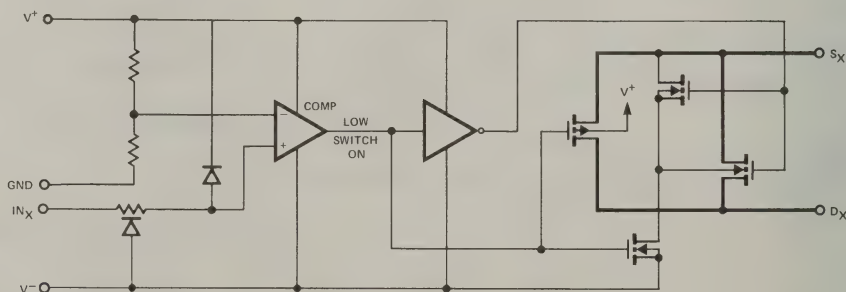
# OIRR-OFF ISOLATION TEST CIRCUIT



# CCRR-CHANNEL TO CHANNEL CROSSTALK TEST CIRCUIT



# SCHEMATIC DIAGRAM (typical channel)



# Quad Monolithic SPST CMOS Analog Switch *designed for . . .*



DG202

- Analog Multiplexing
- Remote Switching under TTL Logic Control
- Servo Control Switching
- Sampled Data Systems
- Programmable Gain Amplifiers

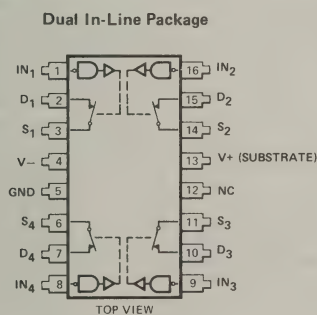
## BENEFITS

- **Environmentally Rugged**
  - 44 V Power Supply Max Rating
  - Static Protected Logic Inputs
  - Latch Proof
- **Easily Interfaced**
  - TTL and CMOS Compatible Without Pullup Resistors
  - Logic Inputs Accept  $\pm$  Comparator Transitions Without Series Current Limiting Resistors
- **Pin for Pin Compatible With**
  - Intersil IH202
  - National LF11202

## DESCRIPTION

The DG202 designed on the Siliconix PLUS-40 CMOS process provides solid state switch action with 175 ohms contact resistance and very high OFF resistance. True switch action takes place over the full analog signal range of  $\pm 15$  V, with BREAK-BEFORE-MAKE operation to prevent momentary shorting of signals inputs. Charge injection has been reduced by design to minimize spikes during switching transitions.

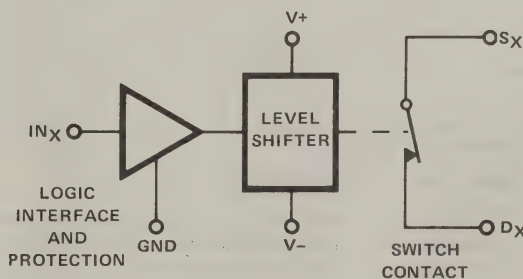
## PIN CONFIGURATION



LOGIC	SWITCH
0	OFF
1	ON

ORDER NUMBERS:  
DG202AK, DG202BK OR DG202CK  
SEE PACKAGE 10  
ORDER NUMBER:  
DG202CJ  
SEE PACKAGE 8  
SWITCH CLOSED FOR LOGIC "1"  
INPUT (POSITIVE LOGIC)

## FUNCTIONAL DIAGRAM (typical switch)



Analog Switches

3

### ABSOLUTE MAXIMUM RATINGS

Voltages referenced to V—

 $V_+ = 44 \text{ V}$ 

GND ..... 25 V

Digital inputs<sup>3</sup>,  $V_S$ ,  $V_D$  .....  $-2\text{ V}$  to  $(V^+ + 2\text{ V})$  or  
20 mA, whichever occurs first

Current, Any Terminal Except S or D..... 30 mA

Continuous Current, S or D ..... 20 mA  
Peak Current S or D

(pulsed at 1 msec, 10% duty cycle max) ..... 70 mA

Storage Temperature (A & B Suffix) . . . . .	- 65 to 150°C
(C Suffix) . . . . .	- 65 to 125°C

## ELECTRICAL CHARACTERISTICS

All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

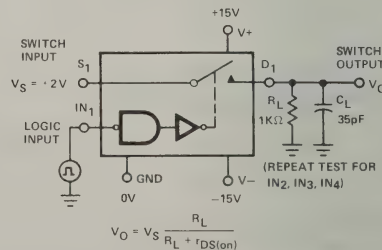
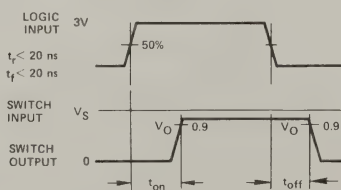
CHARACTERISTIC			TYP <sup>1</sup> 25°C	MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V <sub>+</sub> = 15 V, V <sub>-</sub> = -15 V, GND = 0			
				A SUFFIX			B/C SUFFIX							
				-55°C	25°C	125°C	-20°C/ 0°C	25°C	85°C/ 70°C					
1	S W I T C H	V <sub>ANALOG</sub>	Minimum Analog Signal Handling Capability	± 15		± 15	± 15		± 15	± 15	V			
2		r <sub>DS(on)</sub>	Drain-Source ON Resistance	105	175	175	250	200	200	250	Ω	V <sub>D</sub> = 10 V	V <sub>IN</sub> = 2.4 V, I <sub>S</sub> = -1 mA	
3				115	175	175	250	200	200	250	V <sub>D</sub> = -10 V			
4		I <sub>S(off)</sub>	Source OFF Leakage Current	0.01		1	100		5	100	nA	V <sub>S</sub> = 14 V, V <sub>D</sub> = -14 V	V <sub>IN</sub> = 0.8 V	
5				-0.02		-1	-100		-5	-100		V <sub>S</sub> = -14 V, V <sub>D</sub> = 14 V		
6		I <sub>D(off)</sub>	Drain OFF Leakage Current	0.01		1	100		5	100		V <sub>D</sub> = 14 V, V <sub>S</sub> = -14 V		
7				-0.02		-1	-100		-5	-100		V <sub>D</sub> = -14 V, V <sub>S</sub> = 14 V		
8		I <sub>D(on)</sub> <sup>2</sup>	Drain ON Leakage Current	0.1		1	200		5	200	V <sub>D</sub> = V <sub>S</sub> = 14 V	V <sub>IN</sub> = 2.4 V		
9				-0.15		-1	-200		-5	-200			V <sub>D</sub> = V <sub>S</sub> = -14 V	
10	I N P U T	I <sub>INH</sub>	Input Current, Input Voltage High	-0.0004		-1	-10		-1	-10	μA	V <sub>IN</sub> = 2.4 V		
11		I <sub>INL</sub>	Input Current, Input Voltage Low	-0.0004		-1	-10		-1	-10		V <sub>IN</sub> = 15 V		
12												V <sub>IN</sub> = 0		
13	D Y N A M I C	t <sub>on</sub>	Turn-ON Time	480		600			600		ns	See Switching Time Test Circuit		
14		t <sub>off</sub>	Turn-OFF Time	370		450			450					
15		Q	Charge Injection	20							pC	C <sub>L</sub> = 1000pF, V <sub>GEN</sub> = 0 V, R <sub>GEN</sub> = 0Ω		
16		C <sub>S(off)</sub>	Source OFF Capacitance	5							pF	V <sub>S</sub> = 0, V <sub>IN</sub> = 0 V	f = 140 KHz	
17		C <sub>D(off)</sub>	Drain OFF Capacitance	5								V <sub>D</sub> = 0, V <sub>IN</sub> = 0 V		
18		C <sub>D(on)</sub> + C <sub>S(on)</sub>	Channel ON Capacitance	16								V <sub>D</sub> = V <sub>S</sub> = 0, V <sub>IN</sub> = 5 V		
19		OIRR	Off Isolation	70							dB	V <sub>IN</sub> = 0 V	V <sub>S</sub> = 2 V <sub>pp</sub> , f = 100 KHz, Z <sub>L</sub> = 75Ω	
20		CCRR	Channel to Channel Crosstalk	90										
21		S U P P L Y	I <sub>+</sub>	Positive Supply Current	9		2			2		mA	All Channels "ON" or "OFF," V <sub>IN</sub> = 0 or 2.4 V	
22			I <sub>-</sub>	Negative Supply Current	-3		-1			-1				

NOTES:

1. Typical Values are for DESIGN AID ONLY, not guaranteed and not subject to production testing. 3. Signals on  $S_X$ ,  $D_X$  or  $IN_X$  exceeding  $V+$  or  $V-$  will be clamped by internal diodes. Limit forward diode current to maximum current ratings. ICMC-D

## SWITCHING TIME TEST CIRCUIT

Switch output waveform shown for  $V_S = \text{constant}$  with logic input waveform as shown. Note that  $V_S$  may be + or - as per switching time test circuit.  $V_O$  is the steady state output with switch on. Feedthrough via gate capacitance may result in spikes at leading and trailing edge of output waveform.





# Quad Monolithic SPST CMOS Analog Switch *designed for . . .*



DG211

- **Low Transient Switching**  
i.e., Sample and Hold Circuits
- **Switching Multiple Signals**  
such as Multiplexing Inputs
- **High Frequency Signal**  
Switching e.g., Computer  
Peripheral Equipment
- **TTL Compatible Systems**  
Including Microprocessor  
Systems

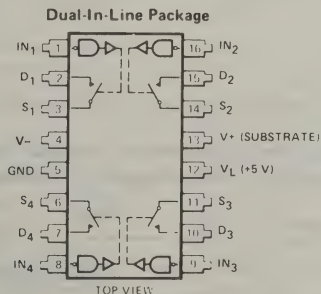
## BENEFITS

- **Environmentally Rugged**
  - Latchproof
  - Power Supply Overvoltage to 40V Max
- **Reduced Switching Error**
  - Low Charge Coupling
- **Easily Interfaced**
  - TTL, DTL and CMOS Compatible without Pull Up Resistors
- **Reduces External Component Requirements**
  - $\pm 15$  V Analog Signal Range with  $\pm 15$  V Supplies
- **Reduced System Cross-Talk**
  - Break-Before-Make Switching
- **Eliminates Signal Error**
  - 0.01 nA Typical Leakage From Source Or Drain
- **Pin for Pin Compatible with**
  - Intersil IH5052, IH201
- **Low Cost**

## DESCRIPTION

The DG211 designed on the Siliconix PLUS-40 CMOS process is a 4-channel single pole single throw analog switch with low and nearly constant ON resistance over the entire analog signal range. The switch will conduct current in either direction with no off-set voltage in the ON condition, and block voltages up to 30 V peak-to-peak in the OFF condition. The ON-OFF state of each switch is controlled by a driver. With a logic "0" at the input to the driver ( $-15$  V to  $0.8$  V) the switch will be ON, and a logic "1" ( $2.4$  V to  $15$  V) will turn the switch OFF. The input can thus be directly interfaced with TTL, DTL, RTL, CMOS and certain PMOS circuits. Switch action is break-before-make. Logic inputs can directly connect to op-amp output swings.

## PIN CONFIGURATION



LOGIC	SWITCH
0	ON
1	OFF

ORDER NUMBER:  
DG211CJ  
SEE PACKAGE 8

SWITCH OPEN FOR LOGIC "1" INPUT (POSITIVE LOGIC)

Analog Switches

3

# ABSOLUTE MAXIMUM RATINGS

V+ to V-	40 V
V <sub>IN</sub> to Ground	V-, V+
V <sub>L</sub> to Ground	-0.3 V, 25 V
V <sub>S</sub> or V <sub>D</sub> to V+	0, -40 V
V <sub>S</sub> or V <sub>D</sub> to V-	0, 40 V
V+ to Ground	25 V
V- to Ground	-25 V
Current, Any Terminal Except S or D	30 mA
Continuous Current, S or D	20 mA
Peak Current, S or D (pulsed at 1 msec, 10% duty cycle max)	70 mA

Storage Temperature ..... -65 to 125°C  
Operating Temperature ..... 0 to 70°C  
Power Dissipation (Package)\* ..... 470 mW  
16 Pin Plastic DIP\*\*  
\*Device mounted with all leads soldered or welded to PC board.  
\*\*Derate 6.5 mW/°C above 25°C

**ELECTRICAL CHARACTERISTICS** All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

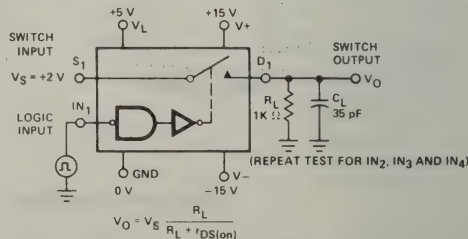
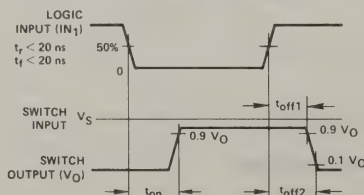
CHARACTERISTIC				TYP1 25°C	MAX LIMITS C SUFFIX 25°C	UNIT	TEST CONDITIONS, UNLESS NOTED: V+ = 15 V, V- = -15 V, Gnd = 0, V <sub>L</sub> = 5 V	
1	S W I T C H	V <sub>ANALOG</sub>	Min. Analog Signal Handling Capability	±15	±15	V		
2		r <sub>DS(on)</sub>	Drain Source ON Resistance	105	175	Ω	V <sub>D</sub> = 10 V V <sub>D</sub> = -10 V	V <sub>IN</sub> = 0.8 V, I <sub>S</sub> = -1 mA
3		I <sub>S(off)</sub>	Source OFF Leakage Current	0.01	5	nA	V <sub>S</sub> = 14 V, V <sub>D</sub> = -14 V V <sub>S</sub> = -14 V, V <sub>D</sub> = 14 V	
4		I <sub>D(off)</sub>	Drain OFF Leakage Current	0.01	5		V <sub>D</sub> = 14 V, V <sub>S</sub> = -14 V V <sub>D</sub> = -14 V, V <sub>S</sub> = 14 V	V <sub>IN</sub> = 2.4 V
5		I <sub>D(on)</sub> <sup>2</sup>	Drain ON Leakage Current	-0.15	-5		V <sub>D</sub> = V <sub>S</sub> = 14 V V <sub>D</sub> = V <sub>S</sub> = -14 V	
6		I <sub>INH</sub>	Input Current, Input Voltage High	-0.0004	-1	μA	V <sub>IN</sub> = 2.4 V V <sub>IN</sub> = 15 V	See Switching Time Test Circuit
7		I <sub>INL</sub>	Input Current, Input Voltage Low	-0.0004	-1		V <sub>IN</sub> = 0	
8		t <sub>on</sub>	Turn-ON Time	460	1000	ns	V <sub>S</sub> = 2 V R <sub>L</sub> = 1K Ω C <sub>L</sub> = 35 pF	
9		t <sub>off1</sub>	Turn-OFF Time	360	500		V <sub>S</sub> = 0, V <sub>IN</sub> = 5 V V <sub>D</sub> = 0, V <sub>IN</sub> = 5 V	f = 1 MHz
10	D Y N A M I C	t <sub>off2</sub>	Turn-OFF Time	450		pF	V <sub>D</sub> = V <sub>S</sub> = 0, V <sub>IN</sub> = 0	
11		C <sub>S(off)</sub>	Source OFF Capacitance	5				
12		C <sub>D(off)</sub>	Drain OFF Capacitance	5		dB		
13		C <sub>D(on)</sub> + C <sub>S(on)</sub>	Channel ON Capacitance	16				
14		OFF Isolation <sup>3</sup>		70			V <sub>IN</sub> = 5 V, R <sub>L</sub> = 1K Ω, C <sub>L</sub> = 15 pF V <sub>S</sub> = 1 V <sub>RMS</sub> , f = 100 kHz	
15	S U P	Interchannel Crosstalk Isolation		90				
16		I+	Positive Supply Current	0.35	0.48	mA	V <sub>IN</sub> = 0 or 2.4 V	
17		I-	Negative Supply Current	0.30	0.48			
18		I <sub>L</sub>	Logic Supply Current	0.5	1.2			

- Typical values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.
- I<sub>D(on)</sub> is leakage from driver into ON switch.
- OFF Isolation =  $20 \log \frac{|V_S|}{|V_D|}$ , V<sub>S</sub> = input to OFF switch, V<sub>D</sub> = output.

ICMC-A

## SWITCHING TIME TEST CIRCUIT

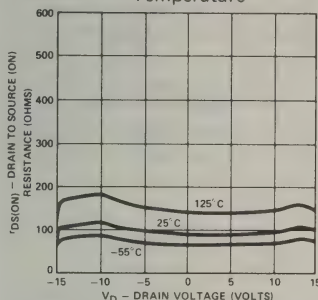
Switch output waveform shown for V<sub>S</sub> = constant with logic input waveform as shown. Note that V<sub>S</sub> may be + or - as per switching time test circuit. V<sub>O</sub> is the steady state output with switch on. Feedthrough via gate capacitance may result in spikes at leading and trailing edge of output waveform.



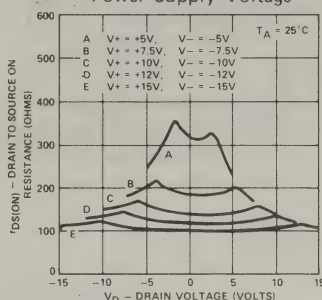
# TYPICAL CHARACTERISTICS

The electrical characteristic table guarantees the DG211 for operation at  $\pm 15$  V,  $\pm 10\%$ ; however, functional operation occurs over the designed range of  $\pm 5$  V to  $\pm 20$  V power supplies. These characteristic graphs show the effect of device parameters over several parameter permutations including power supply variations. These graphs are for design aid only and are not subject to production testing.

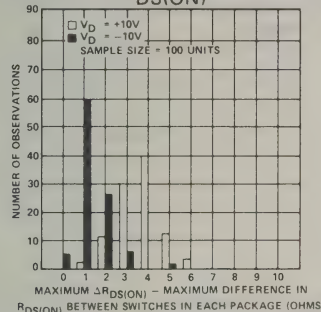
$r_{DS(ON)}$  vs  $V_D$   
Temperature



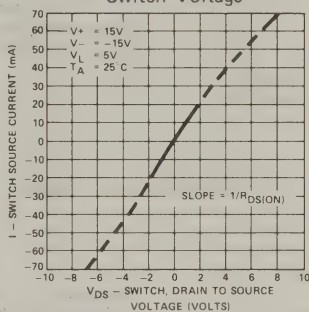
$r_{DS(ON)}$  vs  $V_D$  and  
Power Supply Voltage



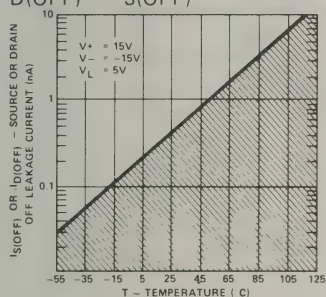
Maximum Channel to Channel  
Variation of  $R_{DS(ON)}$  in Each Device



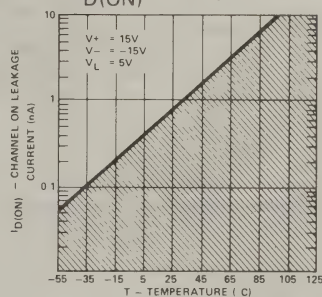
Switch Current vs  
Switch Voltage



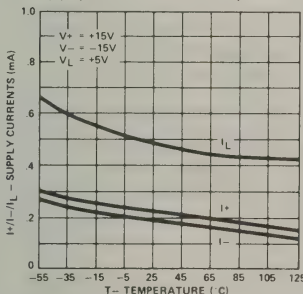
$I_D(OFF)$  or  $I_S(OFF)$  vs Temperature\*



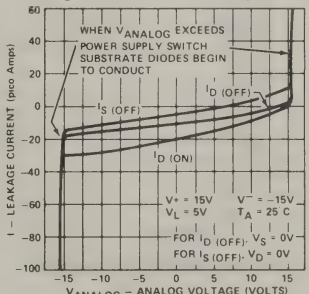
$I_D(ON)$  vs Temperature\*



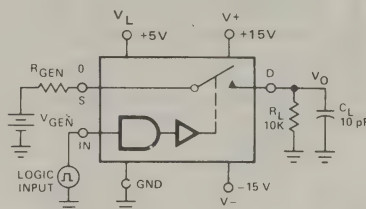
Supply Current vs Temperature



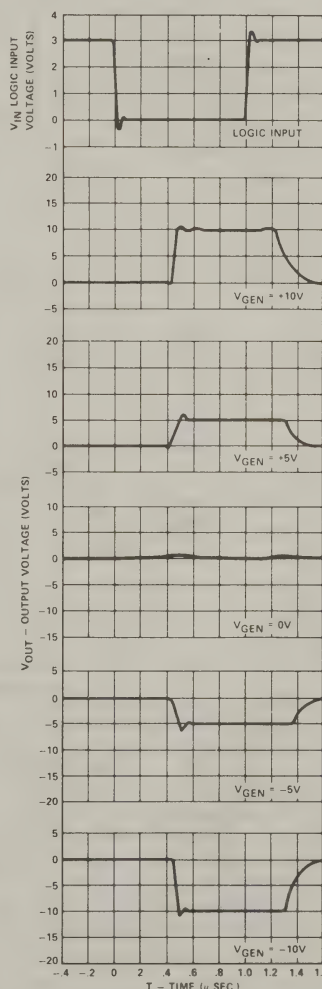
Leakage Current vs Analog Voltage



Typical delay, rise, fall, settling times, and switching transients in this circuit.



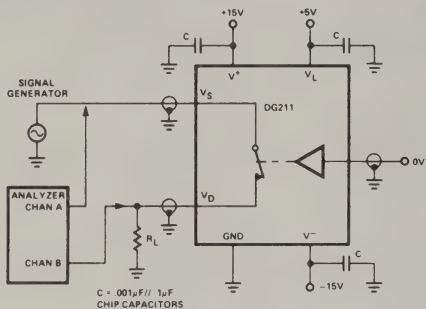
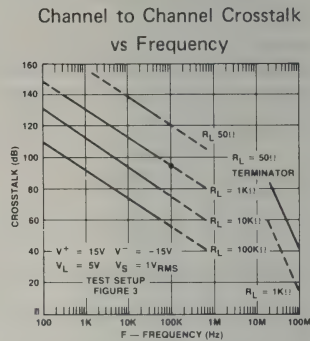
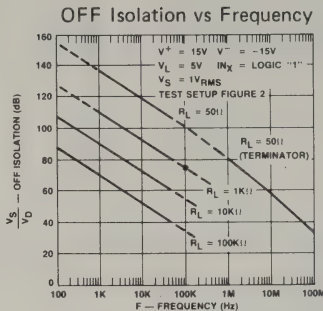
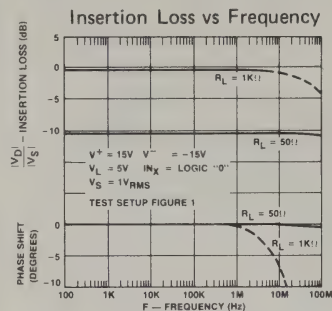
If  $R_{GEN}$ ,  $R_L$  or  $C_L$  is increased, there will be proportional increases in rise and/or fall RC times. Applying  $V_{GEN}$  to D rather than S results in much greater  $t_{ON}$  spikes.



NOTE: Turn-off time is primarily limited here by the RC time constant (50ns) of the load.



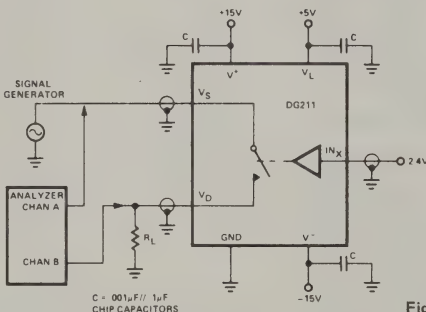
# TYPICAL CHARACTERISTICS (Cont.)



FREQUENCY TESTED	SIGNAL GENERATOR	ANALYZER
100 to 1MHz	WAVETEK MOD 142	HP3575A GAIN-PHASE METER
1M TO 100MHz	TEKTRONIX MOD 191	HPB405A VECTOR VOLT METER

Figure 1

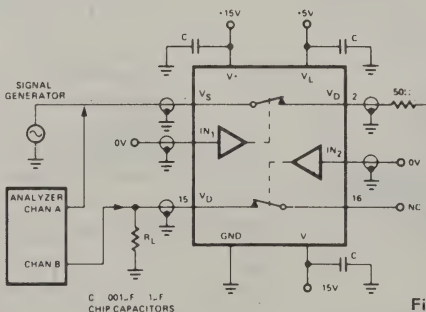
Testing Insertion Loss vs Frequency



FREQUENCY TESTED	SIGNAL GENERATOR	ANALYZER
100 TO 50KHz	HP3580A TRACKING OSC	HP3580A SPECTRUM ANALYZER
1M TO 100MHz	TEKTRONIX MOD 191	HPB405A VECTOR VOLT METER
100K TO 10MHz	HPB568A TRACKING OSC	HPB568A SPECTRUM ANALYZER

Figure 2

Testing OFF Isolation vs Frequency



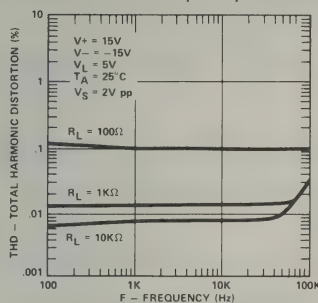
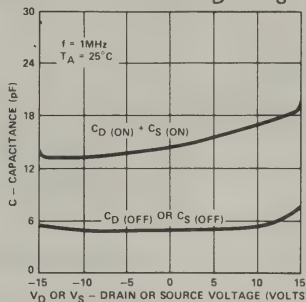
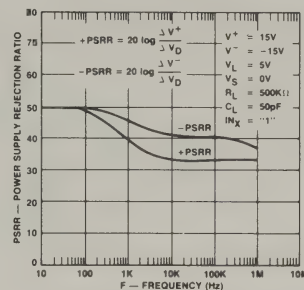
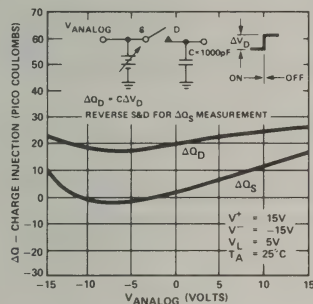
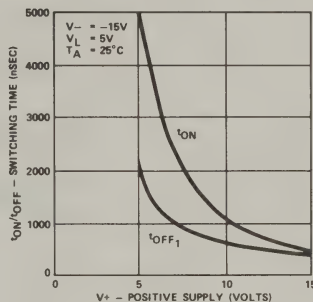
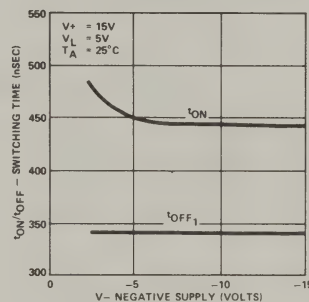
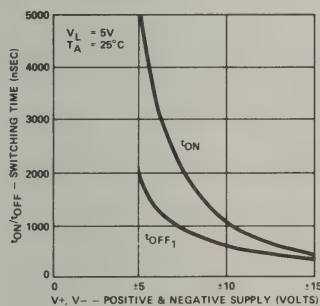
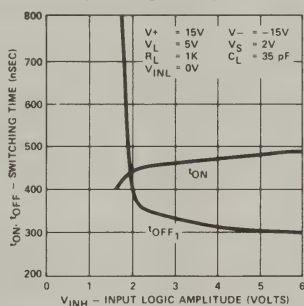
FREQUENCY TESTED	SIGNAL GENERATOR	ANALYZER
100 TO 50KHz	HP3580A TRACKING OSC	HP3580A SPECTRUM ANALYZER
1M TO 100MHz	TEKTRONIX MOD 191	HPB405A VECTOR VOLT METER
100K TO 10MHz	HPB568A TRACKING OSC	HPB568A SPECTRUM ANALYZER

Figure 3

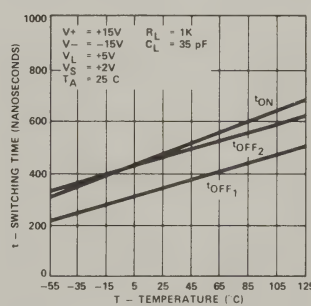
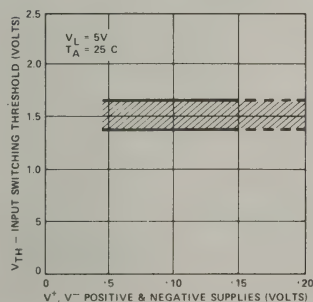
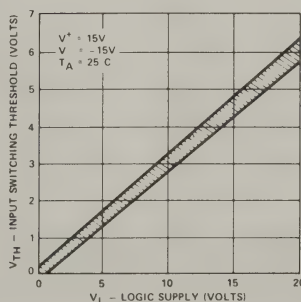
Testing Crosstalk vs Frequency

The data plotted in the frequency response graphs are measured in a special coax test fixture. Each lead of the IC package fits into the center conductor of a solid 50 ohm coax. The fixture eliminates stray capacitance normally encountered in printed circuit (PC) board layouts and sockets. The OFF isolation versus frequency degrades from the values shown with careless PC board layout. The best layout techniques include good ground planes, guardtraces between signal paths and bypassed power supplies.



Total Harmonic Distortion  
vs Frequency

Capacitance vs  $V_D$  or  $V_S$ 

Power Supply Rejection  
vs Frequency

Charge Injection  
vs Analog Voltage

Switching Time vs  
Positive Supply Voltage

Switching Time vs  
Negative Supply Voltage

Switching Time vs Positive &  
Negative Supply Voltage

Switching Time vs  
Input Logic Amplitude


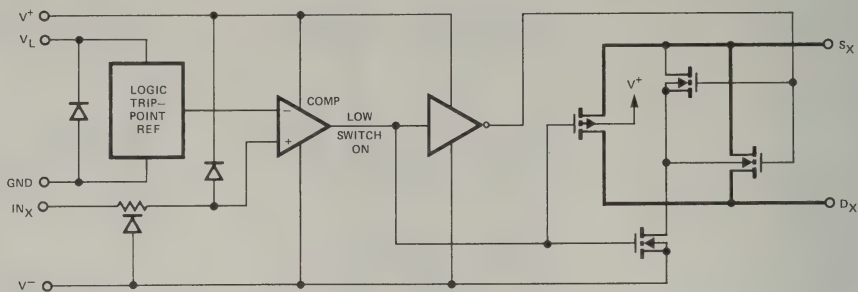
Switching Time vs Temperature


Input Switching Threshold vs  
 $V_+$  &  $V_-$  Supply Voltages

Input Switching Threshold vs  
Logic Supply Voltage


Some applications of the DG211 will find the logic control inputs ( $IN_X$ ) driven from the output of comparators or op-amps with nearly plus to minus 15 volt transitions. In these applications the user can shift the input logic transition voltage from the normal 1.6 V of TTL to zero volts by connecting the  $V_L$  pin to the GND pin. In this mode of operation the input offset voltage between  $IN_X$  and  $V_L$  (= GND) measure less than  $\pm 500mV$ .

$V_L=5V$  presets the input threshold voltage for TTL logic compatibility. Improved noise immunity for CMOS logic compatibility results by connecting  $V_L$  to the  $V_{DD}$  terminal of the CMOS logic.

# SCHEMATIC DIAGRAM (Typical Channel)



## APPLICATIONS

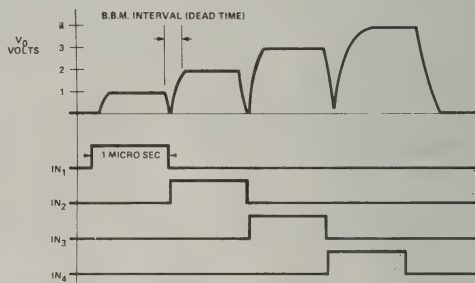
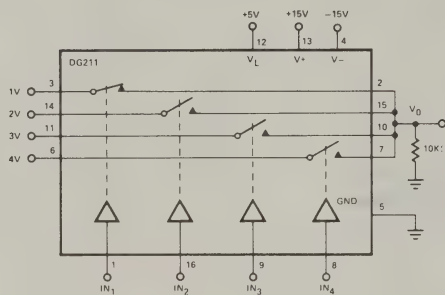


Figure 4. Four Channel Analog Multiplexer

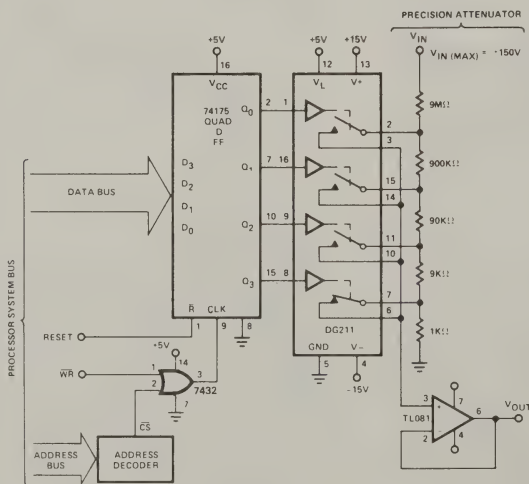


Figure 5. Microprocessor Controlled Analog Signal Attenuator

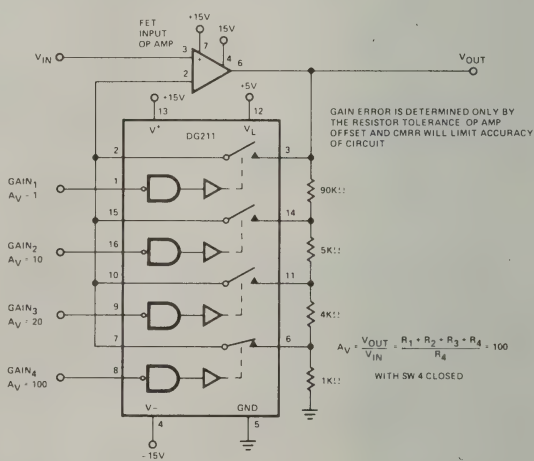


Figure 6. Precision-Weighted Resistor Programmable-Gain Amplifier



# ABSOLUTE MAXIMUM RATINGS

$V_+$ to $V_-$	40 V
$V_{IN}$ to Ground	$V_-$ , $V_+$
$V_L$ to Ground	-0.3 V, 25 V
$V_S$ or $V_D$ to $V_+$	0, -40 V
$V_S$ or $V_D$ to $V_-$	0, 40 V
$V_+$ to Ground	25 V
$V_-$ to Ground	-25 V
Current, Any Terminal Except S or D	30 mA
Continuous Current, S or D	20 mA
Peak Current, S or D (pulsed at 1 msec, 10% duty cycle max)	70 mA

Storage Temperature ..... -65 to 125°C  
 Operating Temperature ..... 0 to 70°C  
 Power Dissipation (Package)\* .....  
 16 Pin Plastic DIP\*\* ..... 470 mW  
 \*Device mounted with all leads soldered or welded to PC board.  
 \*\*Derate 6.5 mW/°C above 25°C

**ELECTRICAL CHARACTERISTICS** All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

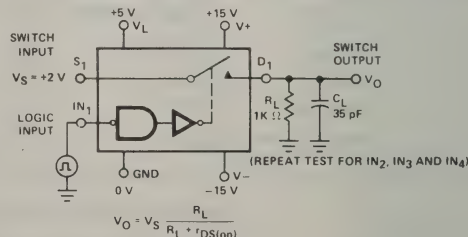
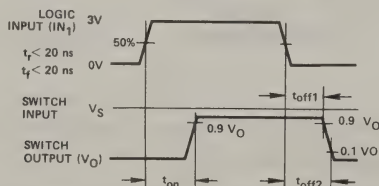
CHARACTERISTIC				TYP1 25°C	MAX LIMITS C SUFFIX 25°C	UNIT	TEST CONDITIONS, UNLESS NOTED: V+ = 15 V, V- = -15 V, Gnd = 0, VL = 5 V	
1	S W I T C H	VANALOG	Min. Analog Signal Handling Capability	±15	±15	V		
2		rDS(on)	Drain Source ON Resistance	105	175	Ω	VD = 10 V	VIN = 2.4 V, IS = -1 mA
3			115	175	VD = -10 V			
4		IS(off)	Source OFF Leakage Current	0.01	5	nA	VS = 14 V, VD = -14 V	VIN = 0.8 V
5			-0.02	-5	VS = -14 V, VD = 14 V			
6		ID(off)	Drain OFF Leakage Current	0.01	5		VD = 14 V, VS = 14 V	
7			-0.02	-5	VD = -14 V, VS = 14 V			
8		ID(on) <sup>2</sup>	Drain ON Leakage Current	0.1	5		VD = VS = 14 V	VIN = 2.4 V
9			-0.15	-5	VD = VS = 14 V			
10	I N P U T	IINH	Input Current, Input Voltage High	-0.0004	1	μA	VIN = 2.4 V	
11			0.003	1	VIN = 15 V			
12		IINL	Input Current, Input Voltage Low	-0.0004	-1		VIN = 0	
13	D Y N A M I C	ton	Turn-ON Time	460	1000	ns	VS = 2 V RL = 1K Ω CL = 35 pF	See Switching Time Test Circuit
14		t <sub>off1</sub>	Turn-OFF Time	360	500			
15		t <sub>off2</sub>	Turn-OFF Time	450				
16		CS(off)	Source OFF Capacitance	5	pF	VS = 0, VIN = 0 V	f = 1 MHz	
17		CD(off)	Drain OFF Capacitance	5		VD = 0, VIN = 0 V		
18		CD(on) + CS(on)	Channel ON Capacitance	16		VD = VS = 0, VIN = 5 V		
19			OFF Isolation <sup>3</sup>	70	dB	VIN = 0 V, RL = 1K Ω, CL = 15 pF VS = 1 V RMS, f = 100 kHz		
20			Interchannel Crosstalk Isolation	90				
21	S U P	I+	Positive Supply Current	0.35	0.48	mA	VIN = 0 or 2.4 V	
22		I-	Negative Supply Current	0.30	0.48			
23		IL	Logic Supply Current	0.5	1.2			

- Typical values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.
- $I_{D(on)}$  is leakage from driver into ON switch.
- OFF Isolation =  $20 \log \frac{|V_S|}{|V_D|}$ .  $V_S$  = input to OFF switch,  $V_D$  = output.

ICMC-C

## SWITCHING TIME TEST CIRCUIT

Switch output waveform shown for  $V_S =$  constant with logic input waveform as shown. Note that  $V_S$  may be + or - as per switching time test circuit.  $V_O$  is the steady state output with switch on. Feedthrough via gate capacitance may result in spikes at leading and trailing edge of output waveform.





# Monolithic General Purpose CMOS Analog Switch

*designed for . . .*

- Programmable Gain Amplifiers
- Analog Multiplexing
- Servo Control Switching



DG243

## BENEFITS

- Transient Suppression
  - Make-Before-Break Switch Operation
- Environmentally Rugged
  - 40V Power Supply Rating
  - Static Protected Logic Inputs
  - Latchproof
- Easily Interfaced
  - TTL and CMOS Compatible without Pull Up Resistors
- Reduces External Component Requirements
  - Full Rail to Rail Analog Signal Range
  - No Diode Protection Required Between  $V_L$  and  $V_+$  for Power Supply Sequencing
- Pin for Pin Compatible with
  - Intersil IH5043
  - Harris HI5043
  - Siliconix DG5043, DG191, DG390

## DESCRIPTION

The DG243 designed on the Siliconix PLUS-40 CMOS process provides solid state switch action with 50 ohms contact resistance and very high OFF resistance. True switch action takes place over the full analog signal range of  $\pm 15$  volts, with Make-Before-Break operation improving transient response in programmable gain amplifiers.

3

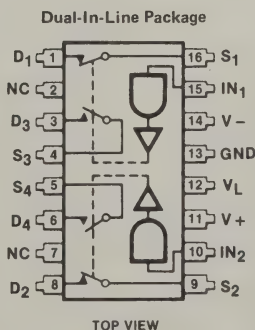
Analog Switches

## PIN CONFIGURATIONS

### DUAL SPDT

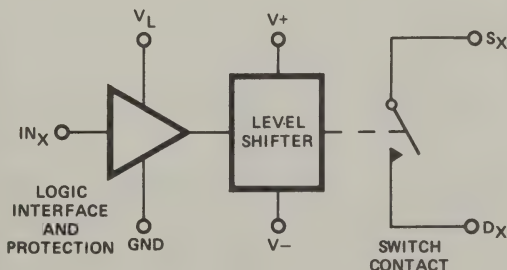
LOGIC	SW 1 SW 2	SW 3 SW 4
0	OFF	ON
1	ON	OFF

ALL SWITCHES SHOWN IN  
THE LOGIC "1"  
SWITCH STATE



ORDER NUMBER:  
DG243AK or DG243CK  
SEE PACKAGE 10  
DG243CJ  
SEE PACKAGE 8

## FUNCTIONAL DIAGRAM (typical channel)



## ABSOLUTE MAXIMUM RATINGS

Voltages referenced to V-

V+ . . . . . 44 V  
 V<sub>L</sub> . . . . . (GND -0.3 V) to 44 V  
 GND . . . . . 25 V  
 Digital inputs<sup>5</sup> V<sub>S</sub>, V<sub>D</sub> . . . . . -2 V to (V<sup>+</sup> +2 V) or  
 30 mA, whichever occurs first.

Current, Any Terminal Except S or D . . . . . 30 mA

Continuous Current, S or D . . . . . 30 mA

Peak Current, S or D

(pulsed at 1 msec, 10% duty cycle max) . . . . . 100 mA

Storage Temperature (A Suffix) . . . . . -65 to 150°C

(C Suffix) . . . . . -65 to 125°C

Operating Temperature (A Suffix) . . . . . -55 to 125°C

(C Suffix) . . . . . 0 to 70°C

Power Dissipation\*

Metal Can and Plastic DIP\*\* . . . . . 450 mW

16 Pin DIP\*\*\*\* . . . . . 900 mW

Flat Pack\*\*\*\*\* . . . . . 900 mW

\*All leads welded or soldered to PC board.

\*\*Derate 6 mW/°C above 75°C

\*\*\*\*Derate 12 mW/°C above 75°C

\*\*\*\*\*Derate 10 mW/°C above 75°C

## ELECTRICAL CHARACTERISTICS

All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTICS			MAX LIMITS						UNIT	TEST CONDITIONS V+ = 15V, V- = -15V VL = 5V, GND = 0V				
			A SUFFIX			C SUFFIX								
			-55°C	25°C	125°C	0°C	25°C	70°C						
1	SWITCH	VANALOG	Minimum Analog Signal Handling Capability		±15	±15		±15	±15	V				
2		rDS(on) <sup>3</sup>	Drain Source ON Resistance	50	50	75	50	50	75	Ω	VD = 10 V, IS = -10 mA	Note 1		
3				50	50	75	50	50	75		VD = -10 V, IS = -10 mA			
4		IS(off) <sup>3</sup>	Source OFF Leakage Current		1	100		1	100	nA	VS = 14 V, VD = -14 V		Note 1	
5				-1	-100		-1	-100	VS = -14 V, VD = 14 V					
6		ID(off) <sup>3</sup>	Drain OFF Leakage Current		1	100		1	100		VS = -14 V, VD = 14 V			
7				-1	-100		-1	-100	VS = 14 V, VD = -14 V					
8		ID(on) <sup>3</sup>	Drain ON Leakage Current		2	200		2	200		VS = VD - 14 V			
9				-2	200		-2	-200	VS = VD = -14 V					
10	INPUT	II NH <sup>3</sup>	Input Current Input Voltage High		±1	±1		±1	±1		μA			VINH = 2.0 V
11		II NL <sup>3</sup>	Input Current Input Voltage Low		±1	±1		±1	±1			VINL = 0.8 V		
12	DYNAMIC	tON <sup>4</sup>	Turn-ON Time		500			700			ns	VS = ±10 V, RL = 1KΩ		Note 2
13		tOFF <sup>4</sup>	Turn-OFF Time		1000			1200		CL = 35 pF				
14		Q	Charge Injection	60 Typical						pC	CL = 1000pF, RGEN = 0Ω, VGEN = 0 V			
15		CS(off)	Source OFF Capacitance	15 Typical						pF	VS = VD = 0 V, f = 1 MHz	Note 1		
16		CD(off)	Drain OFF Capacitance	17 Typical										
17		CD(on) + CS(on)	Channel ON Capacitance	45 Typical										
18		OIRR	OFF Isolation	75 Typical						dB	ZL = 75Ω VS = 2 Vpp f = 1 MHz			
19		CCRR	Interchannel Crosstalk Isolation	89 Typical										
20	SUPPLY	I+ <sup>3</sup>	Positive Supply Current	300	300	300	300	300	300	μA	VIN = 0 V or 2.4 V			
21		I- <sup>3</sup>	Negative Supply Current	-300	-300	-300	-300	-300	-300					
22		IL <sup>3</sup>	Logic Supply Current	300	300	300	300	300	300					
23		IGND	Ground Supply Current	-300	-300	-300	-300	-300	-300					

## NOTES:

- 1: V<sub>IN</sub> = Input voltage to perform proper function.  
 For Logic "1" — V<sub>INH</sub> = 2.0 V  
 For Logic "0" — V<sub>INL</sub> = 0.8 V

- 2: See Switching Time Test Circuit.

- 3: Limits of these parameters are tested 100% at 25°C and 125°C for "/883" devices.

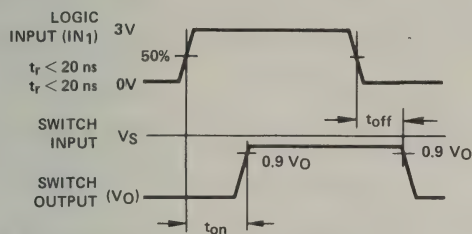
- 4: For "/883" devices these parameters are 100% tested at 25°C.

- 5: Signals on S<sub>X</sub>, D<sub>X</sub> or IN<sub>X</sub> exceeding V<sup>+</sup> or V<sup>-</sup> will be clamped by internal diodes. Limit forward diode current to maximum current ratings.

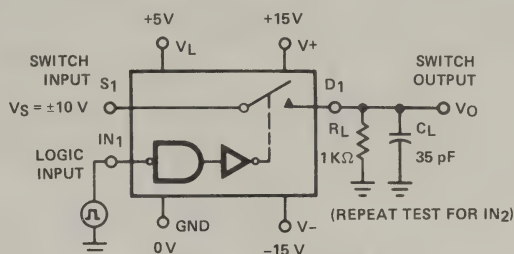
ICMK-C

# SWITCHING TIME TEST CIRCUIT

Switch output waveform shown for  $V_S = \text{constant}$  with logic input waveform as shown. Note that  $V_S$  may be + or – as per switching time test circuit.  $V_O$  is the steady state output with switch on. Feedthrough via gate capacitance may result in spikes at leading and trailing edge of output waveform.

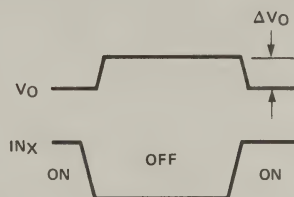
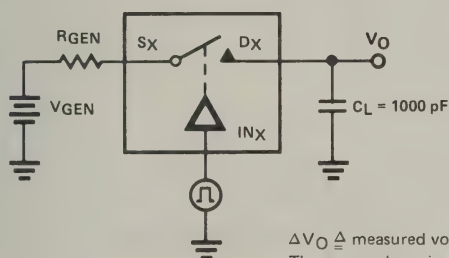


**Note:** Logic input waveform is inverted for switches that have the opposite logic sense control.



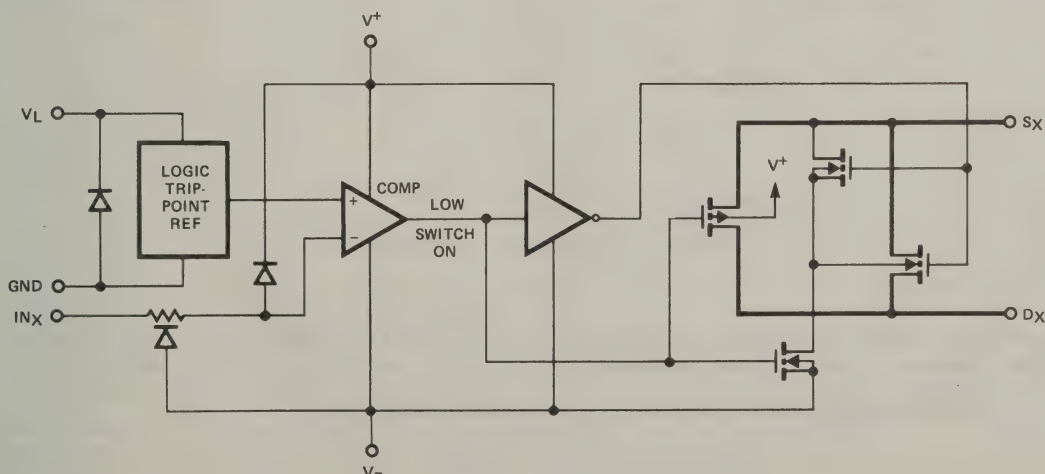
$$V_O = V_S \frac{R_L}{R_L + r_{DS(on)}}$$

# CHARGE INJECTION TEST CIRCUIT



$\Delta V_O \triangleq$  measured voltage error due to charge injection.  
The error voltage in coulombs is  $\Delta Q = C_L \times \Delta V_O$ .

# SCHEMATIC DIAGRAM (typical channel)



# APPLICATIONS

The Make-Before-Break operation of the DG243 provides simple transient suppression in these two important applications.

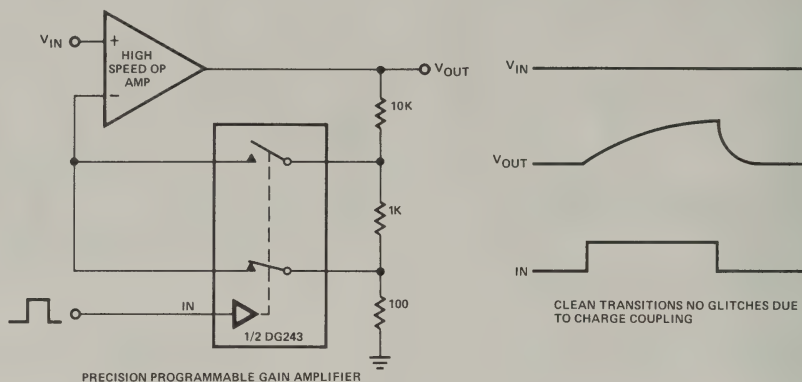


Figure 1. Improving Transient Response in Programmable Gain Amplifiers. "Getting Rid of Glitches".

Figure 1 shows a minimum amount of glitching during changes of gain states. The relatively low impedance of the gain setting resistors 10K, 1K, 100 $\Omega$  shunt the injected charge to ground minimizing transient effects occurring at the inverting input of the op amp. Consequently, these transients are not amplified to  $V_{OUT}$ .

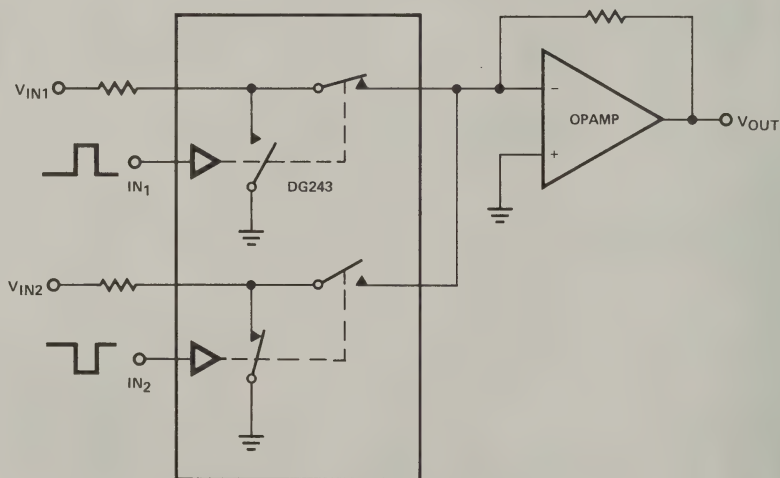


Figure 2. Minimizing Glitches in Audio Switching

Figure 2 takes advantage of the Make-Before-Break operation of the DG243 by shorting transition current to real ground instead of virtual ground. The proper offset voltage specification for op amp selection gives the best results.

The circuit outperforms its Break-Before-Make cousin, the DG5043 in this application.



# Low-Charge Coupling JFET Analog Switches designed for...



- Low Error Sample and Hold Circuits
- 100 MHz Signal Switching with High OFF Isolation
- Presettable Integrators with Minimum Offset Error
- Low Distortion Click Free Audio Switching

## BENEFITS

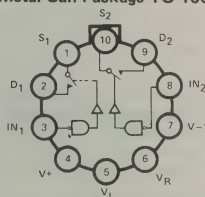
- Minimum Signal Errors
  - Low Charge Feedthrough 7 Picocoulombs Typical
  - Low  $t_{ON} \times I_D(OFF)$  Error Factor
  - Low Leakage Less Than 10 Picoamps Typical
  - Low Distortion — Constant ON Resistance
- Easily Interfaced
  - TTL and CMOS Logic Compatibility Over Full Temperature Range
- Compact Circuit Layouts
  - Several Form Factors Available in Single Packages (eg. 2XSPST, SPDT, 2XSPDT, 2XDPST)

## DESCRIPTION

The DG281 series incorporates N-channel junction-type field-effect transistors (JFETs) designed to function as electronic switches. Level-shifting drivers enable TTL or CMOS outputs to control the ON-OFF state of each switch. The driver is designed to provide break-before-make action when switching from one channel to another. The low switch capacitance results in a minimal amount of charge-feedthrough into the analog signal path. In the ON state each switch conducts current equally well in either direction. In the OFF condition the switches will block voltages up to 22.5 V peak-to-peak.

## PIN CONFIGURATIONS (Top View)

Metal Can Package TO-100

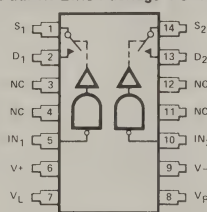


ORDER NUMBERS:  
DG281AA OR DG281BA  
SEE PACKAGE 2

### DUAL SPST

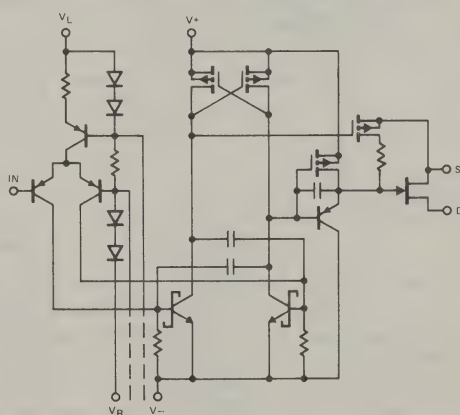
LOGIC	SW 1 & 2
0	ON
1	OFF

## Dual-In-Line Package TO-116

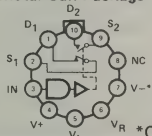


ORDER NUMBERS:  
DG281AP OR DG281BP  
SEE PACKAGE 11

## SCHEMATIC DIAGRAM (Typical Channel)



## Metal Can Package



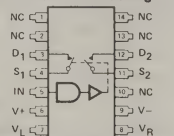
ORDER NUMBERS:  
DG287AA OR DG287BA  
SEE PACKAGE 2

### SPDT

LOGIC	SW 1	SW 2
0	OFF	ON
1	ON	OFF

\*Common to Substrate and Case

## Dual-In-Line Package

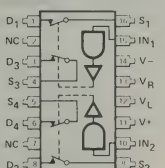


ORDER NUMBERS:  
DG287AP OR DG287BP  
SEE PACKAGE 11

## Dual-In-Line Package

### DUAL DPST

LOGIC	SWITCH
0	OFF
1	ON



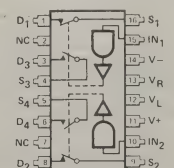
ORDER NUMBERS:  
DG284AP OR DG284BP  
SEE PACKAGE 12

## Dual-In-Line Package

### DUAL SPDT

LOGIC	SW 1	SW 2	SW 3	SW 4
0	OFF	OFF	ON	ON
1	ON	ON	OFF	OFF

SWITCH STATES ARE  
FOR LOGIC "1" INPUT  
(POSITIVE LOGIC)



ORDER NUMBERS:  
DG290AP OR DG290BP  
SEE PACKAGE 12

## APPLICATION HINTS\*

V+	V-	V_L	V_R	V <sub>IN</sub> Logic Input Voltage	V <sub>S</sub> Analog Voltage Range
Positive Supply Voltage (V)	Negative Supply Voltage (V)	Logic Supply Voltage (V)	Reference Supply Voltage (V)	V <sub>INH</sub> Min/ V <sub>INL</sub> Max (V)	
+15**	15	+5	Gnd	2.0/0.8	-7.5 to +15
+10	20	+5	Gnd	2.0/0.8	-12.5 to +10
+12	12	+5	Gnd	2.0/0.8	-4.5 to +12

\*Application Hints are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

\*\*Electrical Parameter Chart based on V+ = +15 V, V- = -15 V, V\_L = 5 V, V\_R = Gnd.

DG281 DG284 DG287 DG290

3  
Analog Switches

# ABSOLUTE MAXIMUM RATINGS

V+ to V-	36 V
V+ to VD	33 V
VD to V-	33 V
VD to VS	±22 V
VL to V-	36 V
VL to VIN	8 V
VL to VR	8 V
VIN to VR	8 V
VR to V-	27 V
VR to VIN	8 V
Current (Any Terminal)	20 mA
Storage Temperature	-65 to +150°C
Operating Temperature (A Suffix)	-55 to +125°C
(B Suffix)	-20 to +85°C

## Power Dissipation\*

Metal Can**	450 mW
14 Pin DIP***	825 mW
16 Pin DIP****	900 mW

\*All leads welded or soldered to PC board.

\*\*Derate 6 mW/°C above 75°C.

\*\*\*Derate 11 mW/°C above 75°C.

\*\*\*\*Derate 12 mW/°C above 75°C.

# ELECTRICAL CHARACTERISTICS

All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC			MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V+ = 15 V, V- = -15 V, VL = 5 V, VR = 0		
			DG281A, DG284A DG287A, DG290A			DG281B, DG284B DG287B, DG290B						
			-55°C	25°C	125°C	-20°C	25°C	85°C				
1	S W I T C H	rDS(on)	Drain Source ON Resistance		300	500		300	500	Ω	VD = -7.5 V	IS = -1 mA††
2		IS(off)	Source OFF Leakage Current		0.5	100		2	100	nA	VS = 7.5 V, VD = -7.5 V	††
3		ID(off)	Drain OFF Leakage Current		0.2	100		1	100		VD = 7.5 V, VS = -7.5 V	
4		ID(on) + IS(on)	Channel ON Leakage Current		-2	-200		-10	-200		VD = VS = -7.5 V	
5	I N	IINL	Input Current, Input Voltage Low	-250	-250	-250	-250	-250	-250	μA	VIN = 0	
6		IINH	Input Current, Input Voltage High		10	20		10	20		VIN = 5 V	
7		ton	Turn-ON Time		150			180		ns	See Switching Time Test Circuit	
8		toff	Turn-OFF Time		130			150				
9	D Y N A M I C	CS(off)	Source OFF Capacitance	6 Typical*						pF	VS = -5 V, ID = 0	f = 1 MHz
10		CD(off)	Drain OFF Capacitance	2 Typical*							VD = -5 V, IS = 0	
11		CD(on) + CS(on)	Channel ON Capacitance	14-17 Typical*							VD = VS = 0	
12		ΔQ	Charge- Feedthrough	11 Typical*							VS = 7.5 V,	
13			4 Typical						VS = -7.5 V			

# POWER SUPPLY CURRENTS

CHARACTERISTIC 25°C MAX LIMITS			DG281	DG284	DG287	DG290	UNIT	TEST CONDITIONS	
14	S U P P L Y	I+	Positive Supply Current	1.5	3	0.8	1.5	mA	VIN = 0†
15		I-	Negative Supply Current	-5	-5.5	-3	-5		
16		IL	Logic Supply Current	4.5	4.5	3.2	4.5		
17		I+	Positive Supply Current	1.5	0.1	0.8	1.5	mA	VIN = 5 V†
18		I-	Negative Supply Current	5	-4	-3	-5		
19		IL	Logic Supply Current	4.5	4.5	3.2	4.5		
20		IR	Reference Supply Current	2	2	2	-2		Both VIN = 5 V, VIN = 0

†If driver has two channels, both are active.

\*Typical values are to DESIGN AID ONLY, not guaranteed and not subject to production testing.

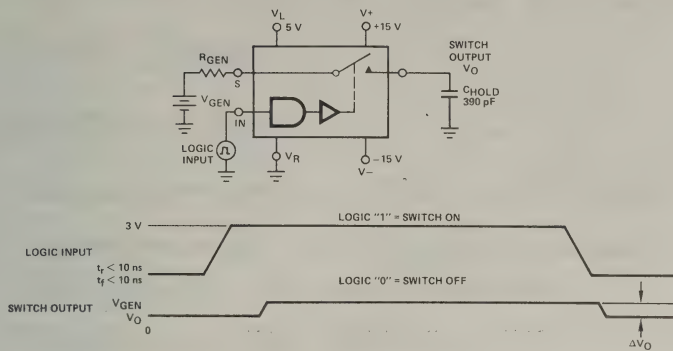
†† Switch being tested ON or OFF as indicated. Input Logic Low 0.8 V.  
Input Logic High 2V.

DG281	CMJB-NH
DG284	CMJA-NH
DG287	CMJC-NH
DG290	CMJB-NH

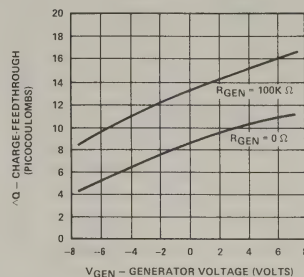
# TRUTH TABLE

DEVICE	IN 1	SW 1	SW 3	IN 2	SW 2	SW 4
DG281	0.8 V	ON	-	0.8 V	ON	-
	2.0 V	OFF	-	2.0 V	OFF	-
DG284	0.8 V	OFF	OFF	0.8 V	OFF	OFF
	2.0 V	ON	ON	2.0 V	ON	ON
DG287	0.8 V	OFF	-	-	ON	-
	2.0 V	ON	-	-	OFF	-
DG290	0.8 V	OFF	ON	0.8 V	OFF	ON
	2.0 V	ON	OFF	2.0 V	ON	OFF

## CHARGE INJECTION TEST CIRCUIT



## Charge Feedthrough vs $R_{GEN}$ and $V_{GEN}$

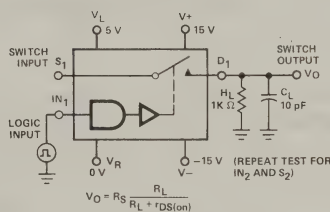
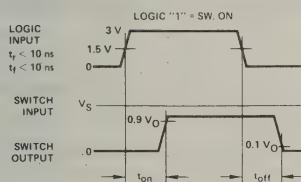


$\Delta V_O = \text{ERROR VOLTAGE GENERATED ACROSS CAPACITOR}$   
 $\Delta Q = \text{CHARGE INJECTED BY SWITCH DURING TURN-OFF}$   
 $\Delta V_O = \Delta Q \times C_{HOLD}$

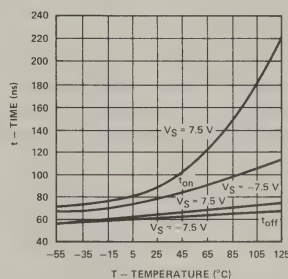
## SWITCHING TIME TEST CIRCUIT

Switch output waveform shown for  $V_S = \text{constant}$  with logic input waveform as shown. Note that  $V_S$  may be + or - as per switching time test circuit.  $V_O$  is the steady state

output with switch on. Feedthrough via gate capacitance may result in spikes at leading and trailing edge of output waveform.

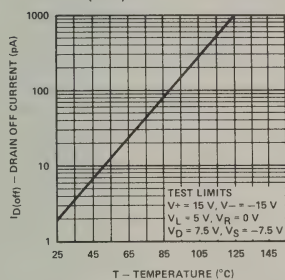


## Switching Time vs $V_S$ and Temperature

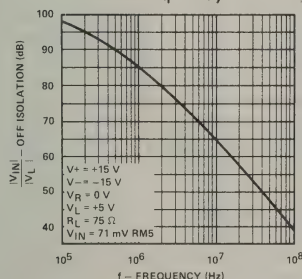


## TYPICAL PERFORMANCE CURVES

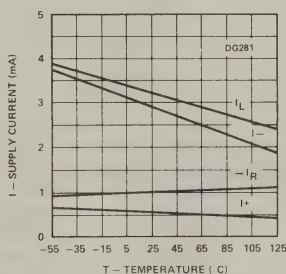
### $I_{D(off)}$ vs. Temperature



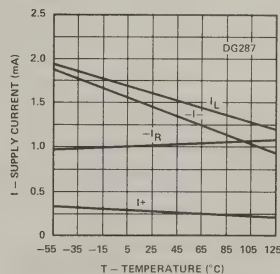
### "OFF" Isolation vs Frequency



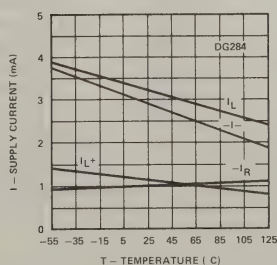
### Supply Current vs Temperature



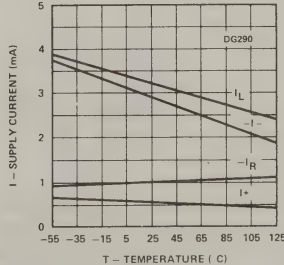
### Supply Current vs Temperature



### Supply Current vs Temperature

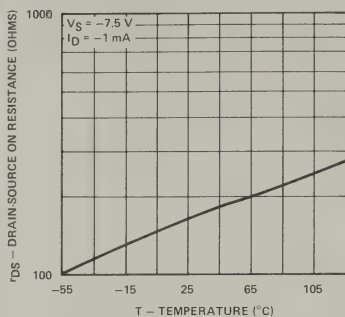


### Supply Current vs Temperature

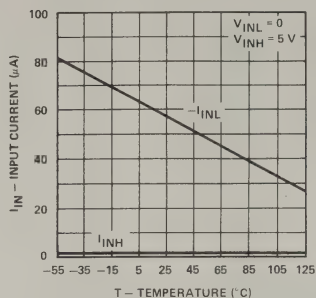




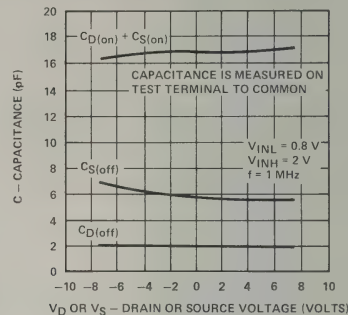
$r_{DS(on)}$  vs Temperature



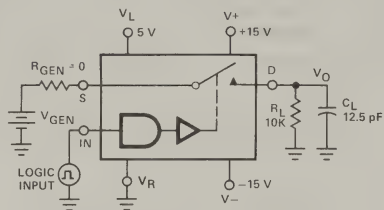
$I_{IN}$  vs  $V_{IN}$  and Temperature



Capacitance vs  $V_D$  or  $V_S$

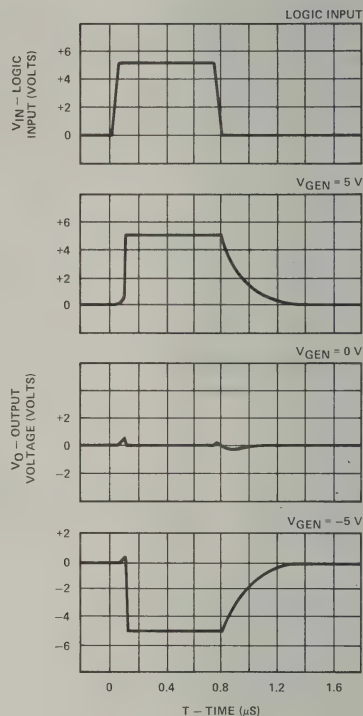
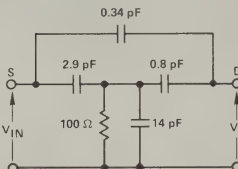


## TYPICAL SWITCHING TRANSIENTS

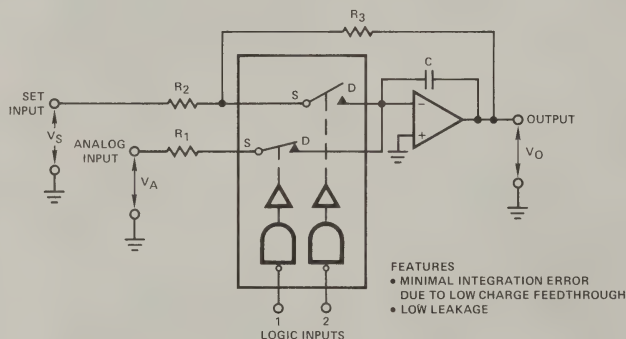


If  $R_{GEN}$ ,  $R_L$  or  $C_L$  is increased, there will be proportional increases in rise and/or fall times.

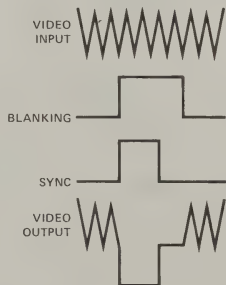
Equivalent "OFF" Circuit



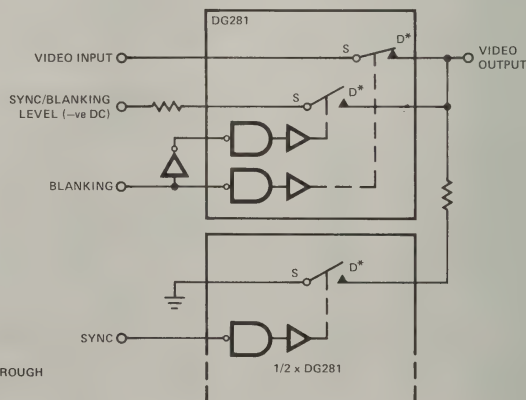
## Application: THREE MODE INTEGRATOR



## Application: VIDEO/BLANKING/SYNC. SIGNAL COMBINER



- FEATURES
- MINIMAL OUTPUT SPIKES DUE TO LOW CHARGE FEEDTHROUGH
  - NEGLIGIBLE FEEDTHROUGH DURING BLANKING INTERVAL





# Monolithic CMOS Analog Switches

designed for . . .

- **Portable, Battery Operated Circuits**
- **Low Leakage Switching**  
i.e. Sample and Hold Circuits
- **Communication Systems**
- **Low Level Switching Circuits**
- **Fast Switching Circuits**  
such as Multiplexers
- **Standard Linear Dual Supply Voltages or Single Supply Systems**



DG300 DG307 Series

## BENEFITS

- **Environmentally Rugged**
  - Latchproof CMOS
- **Low Standby Power**
  - 0.06  $\mu$ W Typical
- **Minimizes Signal Error**
  - 0.1 nA Typical Leakage
- **Low Operating Power**
  - 0.06  $\mu$ W Typical for DG304-307
- **Reduced Voltage Drop Across Switch in ON Condition**
  - $r_{ds(on)} < 50 \Omega$
- **Minimizes Switching Time**
  - $T_{yp} t_{on} \& t_{off} < 180$  ns
- **Minimizes System Power Requirements**
  - Single Supply Operation Capabilities
- **Easily Interfaced**
  - TTL, DTL and CMOS Input Compatible
- **Reduces External Component Requirements**
  - Logic Input Overvoltage Protection

## DESCRIPTION

The DG300 through DG307 switch family features four switching functions using CMOS technology for low and nearly constant ON resistance (less than 50  $\Omega$ ) over the full analog signal range. In the ON condition the switches will conduct current in either direction with no offset voltage. With low power dissipation, (a few milliwatts for the DG300-303, a few hundred microwatts for the DG304-307), this series of switches becomes an ideal candidate for battery-powered or remote switching applications. The switching speed is among the fastest available with the low quiescent power dissipation. In the OFF condition, the switches will block voltages up to 30 V peak-to-peak. A logic input driver controls the ON/OFF state of the switches. (See the "Pin Configuration" for switch status with a logic "1" input.) The DG300-303 switches are TTL and CMOS input compatible and have a logic "0" state with an input less than 0.8 V and a logic "1" state with an input greater than 4.0 V. A pull-up resistor should be added for totem pole TTL outputs. The DG304-307 switches are CMOS input compatible and have a logic "0" state with an input less than 3.5 V and a logic "1" state with an input greater than 11 V (for 15 V positive supply). The logic inputs are protected against overvoltage up to 18 V above and 36 V below the positive supply. The combination of low cost, low power, low resistance and fast speed optimizes system design.

## PIN CONFIGURATIONS

### DUAL SPST DG300 or DG304

Metal Can Package    Dual-In-Line and Flat Package

V+ (SUBSTRATE AND CASE)

TOP VIEW

ORDER NUMBERS:  
DG300AA OR DG300BA  
DG304AA OR DG304BA  
SEE PACKAGE 2

LOGIC	SWITCH
0	OFF
1	ON

ORDER NUMBERS:  
DG300AP OR DG300BP  
DG304AP OR DG304BP  
SEE PACKAGE 11  
DG300CJ  
DG304CJ  
SEE PACKAGE 7  
DG300AL OR DG304AL  
SEE PACKAGE 16

### SPDT DG301 or DG305

Dual-In-Line and Flat Package    Metal Can Package

V+ (SUBSTRATE AND CASE)

TOP VIEW

ORDER NUMBERS:  
DG301AP OR DG301BP  
DG305AP OR DG305BP  
SEE PACKAGE 11  
DG301CJ  
DG305CJ  
SEE PACKAGE 7  
DG301AL OR DG305AL  
SEE PACKAGE 16

LOGIC	SW 1	SW 2
0	OFF	ON
1	ON	OFF

ORDER NUMBERS:  
DG301AA OR DG301BA  
DG305AA OR DG305BA  
SEE PACKAGE 2

### DUAL DPST DG302 or DG306

Dual-In-Line and Flat Package

TOP VIEW

ORDER NUMBERS:  
DG302AP OR DG302BP  
DG306AP OR DG306BP  
SEE PACKAGE 11  
DG302CJ  
DG306CJ  
SEE PACKAGE 7  
DG302AL OR DG306AL  
SEE PACKAGE 16

LOGIC	SWITCH
0	OFF
1	ON

### DUAL SPDT DG303 or DG307

Dual-In-Line and Flat Package

TOP VIEW

ORDER NUMBERS:  
DG303AP OR DG303BP  
DG307AP OR DG307BP  
SEE PACKAGE 11  
DG303CJ  
DG307CJ  
SEE PACKAGE 7  
DG303AL OR DG307AL  
SEE PACKAGE 16

LOGIC	SW 1	SW 2	SW 3	SW 4
0	OFF	ON	ON	OFF
1	ON	OFF	OFF	ON

SWITCH STATES ARE FOR LOGIC "1" INPUTS (POSITIVE LOGIC)

Analog Switches

3

# ABSOLUTE MAXIMUM RATINGS

$V_{IN}$ to Ground	$V^+ +18\text{ V}, V^+ -36\text{ V}$
$V_S$ or $V_D$	$V^+$ to $V^-$
$V^+$ to Ground	+36 V
$V^+$ to $V^-$	+36 V
Current, Any Terminal (Except S or D)	30 mA
Current, S or D, Continuous	30 mA
Pulsed 1 ms 10% Duty Cycle	100 mA
Operating Temperature (A Suffix)	-55 to +125°C
(B Suffix)	-20 to +85°C
(C Suffix)	0 to +70°C
Storage Temperature (A & B Suffix)	-65 to +150°C
(C Suffix)	-65 to +125°C

## Power Dissipation\*

14 Pin Sidebrazed DIP (P)**	825 mW
14 Pin Plastic DIP (J)***	470 mW
Metal Can (A)****	450 mW
Flat Package (L)*****	750 mW

\*Device mounted with all leads welded or soldered to PC board.

\*\*Derate 11 mW/°C above 75°C

\*\*\*Derate 6.5 mW/°C above 25°C

\*\*\*\*Derate 6 mW/°C above 75°C

\*\*\*\*\*Derate 10 mW/°C above 75°C

# ELECTRICAL CHARACTERISTICS

All DC parameters are 100% tested at 25°C. Lots are sample tested for AC parameters and high and low temperature limits to assure conformance with specifications.

Characteristics				Typ <sup>1</sup> 25°C	Max Limits						Unit	Test Conditions V+ = +15 V, V- = -15 V, Gnd = 0 V	
					A/B Suffix			C Suffix					
					-55°C/ -20°C	25°C	125°C/ 85°C	0°C	25°C	70°C			
1	SWITCH	V <sub>ANALOG</sub>	Minimum Analog Signal Handling Capability	±15		±15	±15		±15	±15	V	Switch ON I <sub>S</sub> = 10 mA	
2		r <sub>DS(on)</sub>	Drain Source ON Resistance	30	50	50	75	50	50	75	Ω	V <sub>D</sub> = +10 V, I <sub>S</sub> = -10 mA	Note 2
3				30	50	50	75	50	50	75		V <sub>D</sub> = -10 V, I <sub>S</sub> = +10 mA	
4		I <sub>S(off)</sub>	Source OFF Leakage Current	0.1		1	100		5	100	nA	V <sub>S</sub> = +14 V, V <sub>D</sub> = -14 V	Note 2
5				-0.1		-1	-100		-5	-100		V <sub>S</sub> = -14 V, V <sub>D</sub> = +14 V	
6		I <sub>D(off)</sub>	Drain OFF Leakage Current	0.1		1	100		5	100		V <sub>D</sub> = +14 V, V <sub>S</sub> = -14 V	
7				-0.1		-1	-100		-5	-100		V <sub>D</sub> = -14 V, V <sub>S</sub> = +14 V	
8		I <sub>D(on)</sub>	Channel ON Leakage Current	0.1		1	100		5	100	nA	V <sub>D</sub> = V <sub>S</sub> = +14 V	Note 2
9			-0.1		-2	-200		-5	-200	V <sub>D</sub> = V <sub>S</sub> = -14 V			
10	INPUTS	I <sub>INH</sub>	Input Current	DG300-303 Only	-0.001	-1	-1	-1	-1		μA	V <sub>IN</sub> = +5.0 V	
11			Input Voltage High	DG300-307 Only	0.001	1	1	1	1			V <sub>IN</sub> = +15 V	
12		I <sub>INL</sub>	Input Current Input Voltage Low	-0.001	-1	-1	-1	-1	-1			V <sub>IN</sub> = 0	
13	DYNAMIC	t <sub>on</sub>	Turn ON Time	DG300-303 Only	150	300					nS	See Switching Time Test Circuit	
14		t <sub>off</sub>	Turn OFF Time			130	250						
15		t <sub>on</sub>	Turn ON Time	DG304-307 Only	110	250							
16		t <sub>off</sub>	Turn OFF Time			70	150						
17		t <sub>on</sub> - t <sub>off</sub>	Break-Before-Make Interval	DG301/303 DG305/307 Only	50						See Break-Before-Make Time Test Circuit		
18		C <sub>S(off)</sub>	Source OFF Capacitance	14							pF	V <sub>S</sub> = 0, Note 2	f = 1 MHz
19		C <sub>D(off)</sub>	Drain OFF Capacitance	14								V <sub>D</sub> = 0, Note 2	
20		C <sub>D(on)</sub> + C <sub>S(on)</sub>	Channel ON Capacitance	40								V <sub>D</sub> = V <sub>S</sub> = 0, Note 2	
21		C <sub>IN</sub>	Input Capacitance	6								V <sub>IN</sub> = 0	
22				3.5								V <sub>IN</sub> = +15 V	
23		OFF Isolation <sup>3</sup>	58							dB	V <sub>IN</sub> = 0, R <sub>L</sub> = 1K Ω, C <sub>L</sub> = +15 pF V <sub>S</sub> = 1 V <sub>RMS</sub> , f = 500 kHz		
24	SUPPLY	I <sub>+</sub>	Positive Supply Current	DG300-303 Only	0.23	1	0.5	0.5		1	mA	V <sub>IN</sub> = 4 V (One Input) (All Other Inputs = 0)	
25		I <sub>-</sub>	Negative Supply Current		-0.001	-10	-10	-100		-100			
26		I <sub>+</sub>	Positive Supply Current		0.001	10	10	100		100			
27		I <sub>-</sub>	Negative Supply Current		-0.001	-10	-10	-100		-100			
28		I <sub>+</sub>	Positive Supply Current	DG304-307 Only	0.001	10	10	100		100	μA	V <sub>IN</sub> = +15 V (All Inputs)	
29		I <sub>-</sub>	Negative Supply Current		-0.001	-10	-10	-100		-100			
30		I <sub>+</sub>	Positive Supply Current		0.001	10	10	100		100			
31		I <sub>-</sub>	Negative Supply Current		-0.001	-10	-10	-100		-100			

## NOTES:

- Typical values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.
- $V_{IN}$  = Input voltage to perform proper function. DG300-303:  $V_{IN}$  - For logic "1" = 4 V, for logic "0" = 0.8 V, DG304-307:  $V_{IN}$  - For logic "1" = 11 V, for logic "0" = 3.5 V
- "OFF" Isolation = 20 log  $V_S/V_D$ ,  $V_S$  = Input to OFF switch,  $V_D$  = Output. Since the DG300-301 and DG304/305 have a N/C pin between S and D, the OFF Isolation generally improves by 7 dB @ 500 KHz over value shown here.

DG300 ICMA-A DG302 ICMB-A

DG301 ICMA-B DG303 ICMB-B

DG304 ICMA-C DG306 ICMB-C

DG305 ICMA-D DG307 ICMB-D

# Monolithic CMOS Analog Switches



*designed for . . .*

- **Portable, Battery Operated Circuits**
- **Low Leakage Switching**  
i.e. Sample and Hold Circuits
- **Communication Systems**
- **Low Level Switching Circuits**
- **Fast Switching Circuits**  
such as Multiplexers
- **Standard Linear Dual Supply Voltages or Single Supply Systems**

## BENEFITS

- **Environmentally Rugged**
  - Latchproof CMOS
- **Low Standby Power**
  - 0.06  $\mu$ W Typical
- **Minimizes Signal Error**
  - 0.1 nA Typical Leakage
- **Low Operating Power**
  - 7.5 mW Typical
- **Reduced Voltage Drop Across Switch in ON Condition**
  - $r_{ds(on)} < 50 \Omega$
- **Minimizes Switching Time**
  - $T_{yp} t_{on} \& t_{off} < 180$  ns
- **Minimizes System Power Requirements**
  - Single Supply Operation Capabilities
- **Easily Interfaced**
  - TTL, DTL / CMOS Input Compatible
  - Pin to Pin Replacement for DG180 Series Switches
- **Reduces External Component Requirements**
  - Logic Input Overvoltage Protection

## DESCRIPTION

The DG381 through DG390 switch family features four switching functions using CMOS technology for low and nearly constant ON resistance (less than  $50 \Omega$ ) over the full analog signal range. In the ON condition the switches will conduct current in either direction with no offset voltage. With low power dissipation, a few milliwatts, this series of switches becomes an ideal candidate for battery-powered or remote switching applications. The switching speed is among the fastest available with the low quiescent power dissipation. In the OFF condition, the switches will block voltages up to 30 V peak-to-peak. A logic input driver controls the ON/OFF state of the switches. (See the "Pin Configuration" for switch status with a logic "1" input.) The switches are TTL and CMOS input compatible and have a logic "0" state with an input less than 0.8 V and a logic "1" state with an input greater than 4.0 V. A pull-up resistor should be added for totem pole TTL outputs. The logic inputs are protected against overvoltage up to 18 V above and 36 V below the positive supply. The combination of low cost, low power, low resistance and fast speed optimizes system design.

## PIN CONFIGURATIONS

<p><b>DUAL SPST DG381</b> Dual-In-Line Package</p> <p>TOP VIEW</p> <p>ORDER NUMBERS: DG381AA OR DG381BA SEE PACKAGE 2</p> <p>SEE PACKAGE 11 DG381CJ SEE PACKAGE 7</p> <p>*(SUBSTRATE AND CASE)</p> <table border="1"> <thead> <tr> <th>LOGIC</th> <th>SW 1</th> <th>SW 2</th> </tr> </thead> <tbody> <tr> <td>0</td> <td>ON</td> <td>ON</td> </tr> <tr> <td>1</td> <td>OFF</td> <td>OFF</td> </tr> </tbody> </table>	LOGIC	SW 1	SW 2	0	ON	ON	1	OFF	OFF	<p><b>SPDT DG387</b> Dual-In-Line Package</p> <p>TOP VIEW</p> <p>ORDER NUMBERS: DG387AP OR DG387BP SEE PACKAGE 11 DG387CJ SEE PACKAGE 7</p> <p>*(SUBSTRATE AND CASE)</p> <table border="1"> <thead> <tr> <th>LOGIC</th> <th>SW 1</th> <th>SW 2</th> </tr> </thead> <tbody> <tr> <td>0</td> <td>OFF</td> <td>ON</td> </tr> <tr> <td>1</td> <td>ON</td> <td>OFF</td> </tr> </tbody> </table>	LOGIC	SW 1	SW 2	0	OFF	ON	1	ON	OFF			
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<p><b>DUAL DPST DG384</b> Dual-In-Line Package</p> <p>TOP VIEW</p> <p>ORDER NUMBERS: DG384AP OR DG384BP SEE PACKAGE 12 DG384CJ SEE PACKAGE 8</p> <p>*(SUBSTRATE AND CASE)</p> <table border="1"> <thead> <tr> <th>LOGIC</th> <th>SW 1-4</th> </tr> </thead> <tbody> <tr> <td>0</td> <td>OFF</td> </tr> <tr> <td>1</td> <td>ON</td> </tr> </tbody> </table>	LOGIC	SW 1-4	0	OFF	1	ON	<p><b>DUAL SPDT DG390</b> Dual-In-Line Package</p> <p>TOP VIEW</p> <p>ORDER NUMBERS: DG390AP OR DG390BP SEE PACKAGE 12 DG390CJ SEE PACKAGE 8</p> <p>*(SUBSTRATE AND CASE)</p> <table border="1"> <thead> <tr> <th>LOGIC</th> <th>SW 1</th> <th>SW 2</th> <th>SW 3</th> <th>SW 4</th> </tr> </thead> <tbody> <tr> <td>0</td> <td>OFF</td> <td>ON</td> <td>ON</td> <td>OFF</td> </tr> <tr> <td>1</td> <td>ON</td> <td>ON</td> <td>OFF</td> <td>OFF</td> </tr> </tbody> </table>	LOGIC	SW 1	SW 2	SW 3	SW 4	0	OFF	ON	ON	OFF	1	ON	ON	OFF	OFF
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0	OFF	ON	ON	OFF																		
1	ON	ON	OFF	OFF																		

SWITCH STATES ARE FOR LOGIC "1" INPUTS (POSITIVE LOGIC)

DG381 DG384 DG387 DG390

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Analog Switches



# ABSOLUTE MAXIMUM RATINGS

$V_{IN}$ to Ground	V+ +18 V, V+ -36 V
$V_S$ to $V_D$	V+, V-
V+ to Ground	+36 V
V+ to V-	+36 V
Current, Any Terminal (Except S or D)	30 mA
Current, S or D, Continuous	30 mA
Pulsed 1 ms 10% Duty Cycle	100 mA
Operating Temperature (A Suffix)	-55 to +125°C
(B Suffix)	-20 to +85°C
(C Suffix)	0 to +70°C
Storage Temperature (A & B Suffix)	-65 to +150°C
(C Suffix)	-65 to +125°C

Power Dissipation\*

Sidebrazed DIP (P)\*\* 825 mW

Plastic DIP (J)\*\*\* 470 mW

Metal Can (A)\*\*\*\* 450 mW

\*Device mounted with all leads welded or soldered to PC board.

\*\*Derate 11 mW/°C above 75°C

\*\*\*Derate 6.5 mW/°C above 25°C

\*\*\*\*Derate 6 mW/°C above 75°C

# ELECTRICAL CHARACTERISTICS

All DC parameters are 100% tested at 25°C. Lots are sample tested for AC parameters and high and low temperature limits to assure conformance with specifications.

Characteristics			Typ <sup>1</sup> 25°C	Max Limits						Unit	Test Conditions V+ = +15 V, V- = -15 V, Gnd = 0 V		
				A/B Suffix			C Suffix						
			-55°C/ -20°C	25°C	125°C/ 85°C	0°C	25°C	70°C					
1	SWITCH	VANALOG Minimum Analog Signal Handling Capability	±15		±15	±15		±15	±15	V	Switch ON I <sub>S</sub> = 10 mA		
2		r <sub>DS(on)</sub> Drain Source ON Resistance	30	50	50	75	50	50	75	Ω	V <sub>D</sub> = +10 V, I <sub>S</sub> = -10 mA	Note 2	
3			30	50	50	75	50	50	75		V <sub>D</sub> = -10 V, I <sub>S</sub> = +10 mA		
4		I <sub>S(off)</sub> Source OFF Leakage Current	0.1		1	100		5	100	nA	V <sub>S</sub> = +14 V, V <sub>D</sub> = -14 V	Note 2	
5			-0.1		-1	-100		-5	-100		V <sub>S</sub> = -14 V, V <sub>D</sub> = +14 V		
6		I <sub>D(off)</sub> Drain OFF Leakage Current	0.1		1	100		5	100	nA	V <sub>D</sub> = +14 V, V <sub>S</sub> = -14 V		
7			-0.1		-1	-100		-5	-100		V <sub>D</sub> = -14 V, V <sub>S</sub> = +14 V		
8		I <sub>D(on)</sub> Channel ON Leakage Current	0.1		1	100		5	100	nA	V <sub>D</sub> = V <sub>S</sub> = +14 V	Note 2	
9			-0.1		-2	-200		-5	-200		V <sub>D</sub> = V <sub>S</sub> = -14 V		
10	IN	I <sub>INH</sub> Input Current	-0.001	-1	-1	-1		-1		μA	V <sub>IN</sub> = +5 V		
11		I <sub>INL</sub> Input Voltage High	0.001	1	1	1		1			V <sub>IN</sub> = +15 V		
12		I <sub>INL</sub> Input Current Input Voltage Low	-0.001	-1	-1	-1		-1			V <sub>IN</sub> = 0		
13	DYNAMIC	t <sub>on</sub> Turn ON Time	150		300					nS	See Switching Time Test Circuit		
14		t <sub>off</sub> Turn OFF Time	130		250						See Break-Before-Make Time Test Circuit		
15		t <sub>on</sub> - t <sub>off</sub> Break-Before-Make Interval DG387/390 only	50										
16		PARAMETER	C <sub>S(off)</sub> Source OFF Capacitance	14							pF	V <sub>S</sub> = 0, Note 2	f = 1 MHz
17			C <sub>D(off)</sub> Drain OFF Capacitance	14								V <sub>D</sub> = 0, Note 2	
18			C <sub>D(on)</sub> + C <sub>S(on)</sub> Channel ON Capacitance	40								V <sub>D</sub> = V <sub>S</sub> = 0, Note 2	
19			C <sub>IN</sub> Input Capacitance	6								V <sub>IN</sub> = 0	
20				3.5								V <sub>IN</sub> = +15 V	
21			OFF Isolation <sup>3</sup>	58							dB	V <sub>IN</sub> = 0, R <sub>L</sub> = 1K Ω, C <sub>L</sub> = +15 pF V <sub>S</sub> = 1 V <sub>RMS</sub> , f = 500 kHz	
22	SUPPLY	I+ Positive Supply Current	0.23	1	0.5	0.5		1		mA	V <sub>IN</sub> = 4 V (One Input) (All Other Inputs = 0)		
23		I- Negative Supply Current	-0.001	-10	-10	-100		-100			μA	V <sub>IN</sub> = 0.8 V (All Inputs)	
24		I+ Positive Supply Current	0.001	10	10	100		100					
25		I- Negative Supply Current	-0.001	-10	-10	-100		-100					

## NOTES:

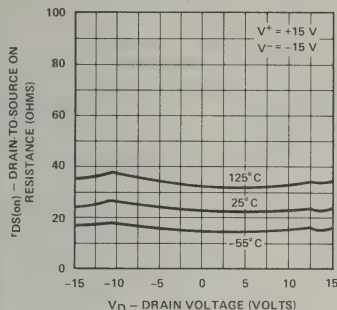
- Typical values are for DESIGN AID ONLY, not guaranteed and not subject to production testing
- $V_{IN}$  = Input voltage to perform proper function,  $V_{IN}$  for logic "1" = 4 V, for logic "0" = 0.8 V
- "OFF" Isolation  $\geq 20 \log V_S/V_D$  = Input to OFF switch,  $V_D$  = Output

DG381 ICMA-E DG384 ICMB A  
DG387 ICMA B DG390 ICMB B

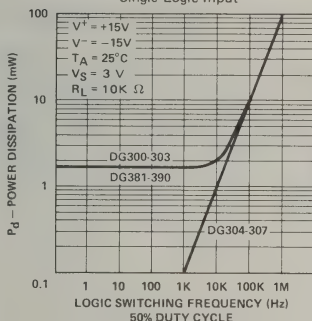


## TYPICAL CHARACTERISTICS

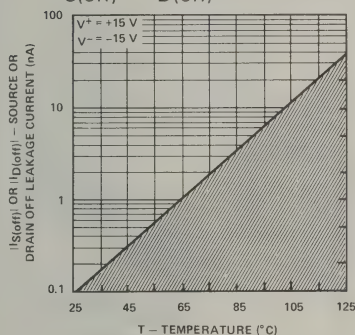
$r_{DS(on)}$  vs  $V_D$  and Temperature



Device Power Dissipation vs Switching Frequency  
Single Logic Input

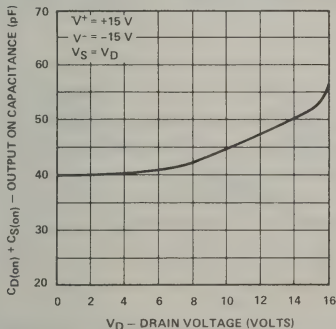


$I_{S(off)}$  or  $I_{D(off)}$  vs Temperature\*

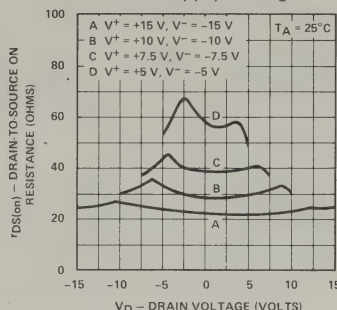


\*The net leakage into the source or drain is the n-channel leakage minus the p-channel leakage. This difference can be positive, negative, or zero depending on the analog voltage and temperature, and will vary greatly from unit to unit.

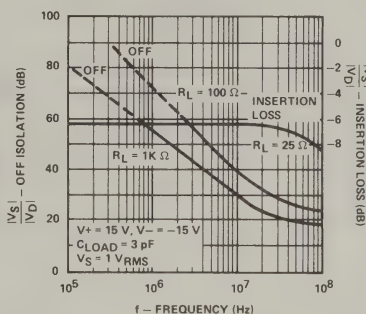
Output ON Capacitance vs Drain Voltage



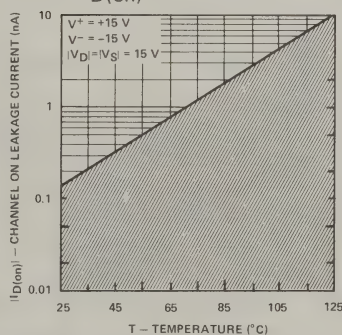
$r_{DS(on)}$  vs  $V_D$  and Power Supply Voltage



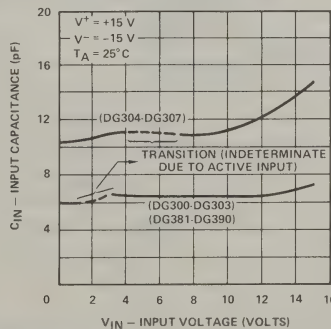
OFF Isolation Insertion Loss vs Frequency



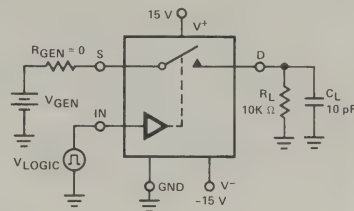
$I_{D(on)}$  vs Temperature\*



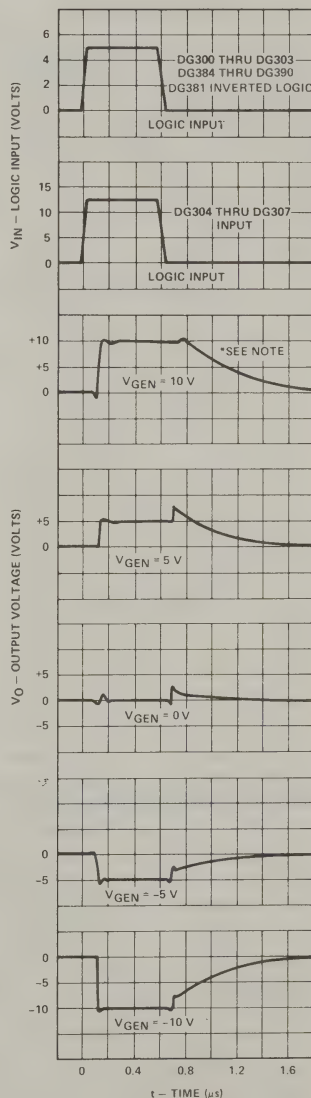
Input Capacitance vs Input Voltage



Typical delay, rise, fall, settling times, and switching transients in this circuit.



If  $R_{GEN}$ ,  $R_L$  or  $C_L$  is increased, there will be proportional increases in rise and/or fall RC times. Applying  $V_{GEN}$  to D rather than S results in much greater spikes.



\*Note: The turn-off time is primarily limited here by the RC time constant (100 ns) of the load.

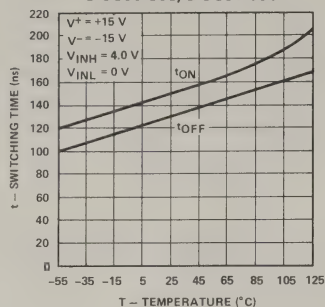
DG300-DG307 DG381-DG390

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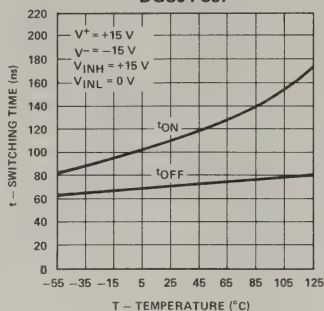
Analog Switches

# TYPICAL CHARACTERISTICS (Cont'd)

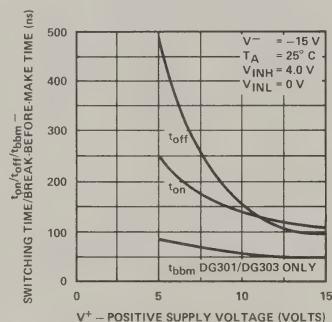
Switching Time vs Temperature  
 DG300-303, DG381-390



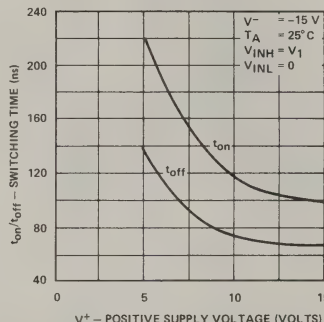
Switching Time vs Temperature  
 DG304-307



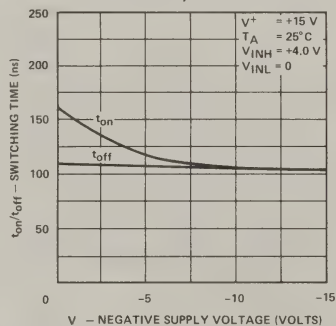
Switching Time and Break-Before-Make Time  
 vs Positive Supply Voltage  
 DG300-303, DG381-390



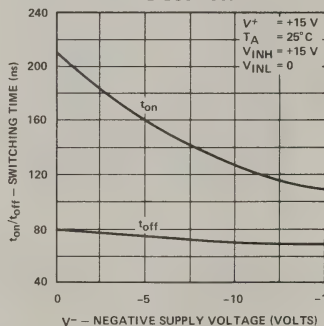
Switching Time  
 vs Positive Supply Voltage  
 DG304-307



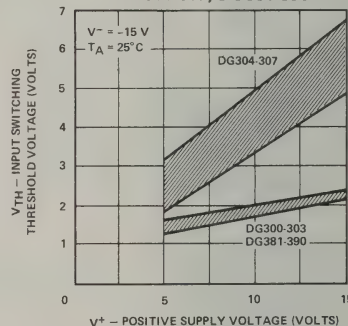
Switching Time  
 vs Negative Supply Voltage  
 DG300-303, DG381-390



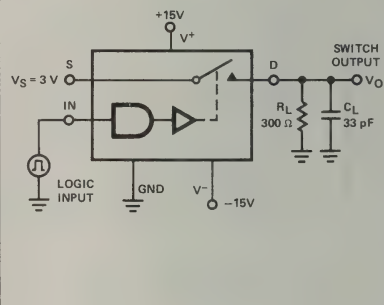
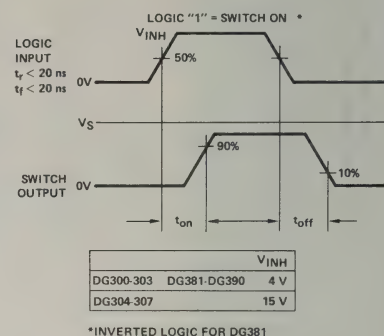
Switching Time  
 vs Negative Supply Voltage  
 DG304-307



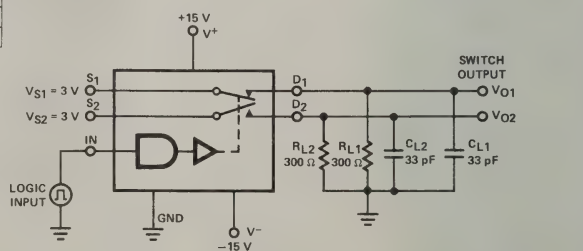
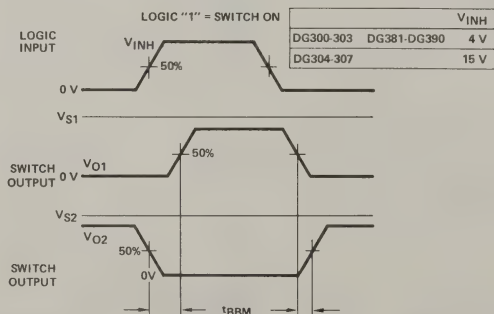
Input Switching Threshold  
 vs Positive Supply Voltage  
 DG300-307, DG381-390

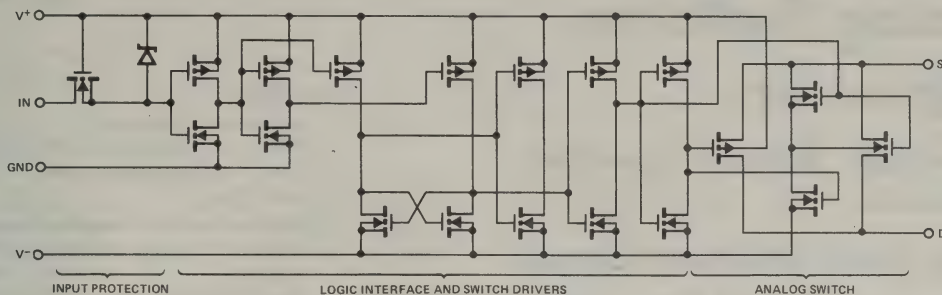


## SWITCHING TIME TEST CIRCUIT (DG300-307 DG381-390)



## BREAK-BEFORE-MAKE TIME TEST CIRCUIT SPDT (DG301, DG303, DG305, DG307, DG384, DG390)



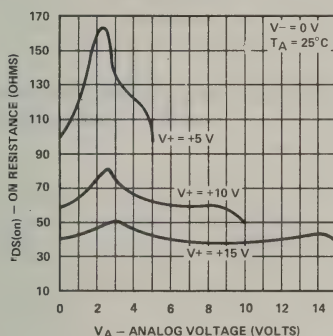


## APPLICATIONS

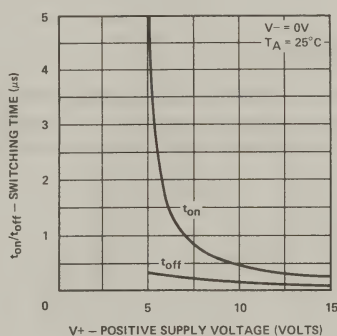
### Single Supply Operation

The DG300 series of analog switches will switch positive analog signals while using a single positive supply. This will allow use in many applications where only one supply is available. The trade-offs or performance given up while using single supplies are: 1) Increased  $r_{DS(ON)}$ ; 2) slower switching speed. Typical curves for aid in designing with single supplies are supplied in the Figures below. As stated in the absolute maximum ratings section of the data sheet, the analog voltage should not go above or below the supply voltages which in single operation are  $V^+$  and 0 volts.

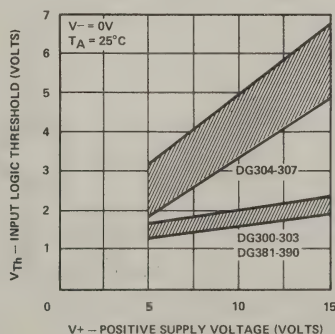
$R_{DS(on)}$  vs Analog and Positive Supply Voltage  
With  $V^- = 0V$



Switching Time vs  $V^+ -$  Positive Supply Voltage



Input Threshold Voltage vs Positive Supply



**Single Supply Range:**  
( $V^-$  and  $GND$  Tied Together)  
 $V^+$ :  $+5V$  to  $+25V$

**Analog Signal Range:**  
 $V^- < V_{ANALOG} \leq V^+$



# Versatile CMOS Analog Switches

*designed for . . .*



- Portable, Battery Operated Circuits
- Low Level Switching Circuits
- Sample and Hold Circuits
- High Speed Switching
- Programmable Gain Amplifiers
- Single or Dual Supply Systems

## BENEFITS

- **Environmentally Rugged**
  - 40 V Power Supply Maximum Rating
  - Static Protected Logic Inputs
  - Latch Proof
- **Minimizes System Power Requirements**
  - Operates Off Single Supply when V- Tied to GND
  - Power Dissipation .06  $\mu$ W Typical DG304A-307A
- **Fast  $t_{on}$  and  $t_{off}$  <110 nsec DG304-DG307A**
- **Minimizes Signal Error**
  - Low  $r_{DS(on)}$  30 ohm Typical
  - Low Leakage 40 pA @ 25°C  
1 nA @ 125°C
  - Full Rail to Rail Analog Signal Range
- **Easily Interfaced**
  - TTL and CMOS Compatible
- **Pin for Pin Compatible With**
  - Harris HI-3XX Family
- **DG381A-DG390A are Pin for Pin Compatible with DG180 Series**

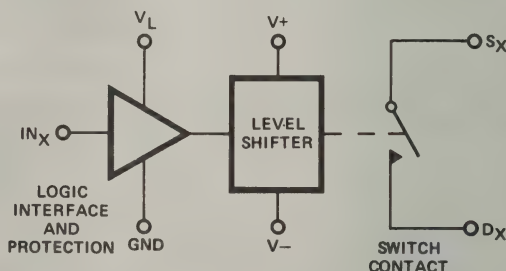
## DESCRIPTION

The DG300A and DG381A series designed on the Siliconix PLUS-40 CMOS process provides solid state switch action with 30 ohms contact (ON) resistance and very high OFF resistance. True bidirectional switch action occurs over the full analog signal range of  $\pm 15V$ , with Break-Before-Make operation to prevent momentary shorting of signal inputs.

## FUNCTIONAL DESCRIPTION

PART NUMBER	TYPE SWITCH	COMPATIBILITY
DG300A	Dual SPST	TTL
DG301A	Dual SPDT	TTL
DG302A	Dual DPST	TTL
DG303A	Dual SPDT	TTL
DG304A	Dual SPST	CMOS
DG305A	Dual SPDT	CMOS
DG306A	Dual DPST	CMOS
DG307A	Dual SPDT	CMOS
DG381A	Dual SPST	TTL
DG384A	Dual DPST	TTL
DG387A	Dual SPDT	TTL
DG390A	Dual SPDT	TTL

## FUNCTIONAL DIAGRAM (typical channel)

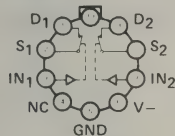




# PIN CONFIGURATIONS

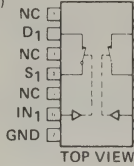
## DUAL SPST DG300A or DG304A

Metal Can Package  
Dual-In-Line and Flat Package



TOP VIEW

ORDER NUMBERS:  
DG300AAA OR DG300ABA  
DG304AAA OR DG304ABA  
SEE PACKAGE 2



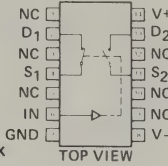
TOP VIEW

LOGIC	SWITCH
0	OFF
1	ON

ORDER NUMBERS:  
DG300AAK OR DG300ABK  
OR DG300ACK  
DG304AAK OR DG304ABK  
OR DG304ACK  
SEE PACKAGE 9  
DG300ACJ  
DG304ACJ  
SEE PACKAGE 7  
DG300AAL OR DG304AAL  
SEE PACKAGE 16

## SPDT DG301A or DG305A

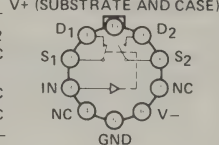
Dual-In-Line and Flat Package Metal Can Package



TOP VIEW

ORDER NUMBERS:  
DG301AAK OR DG301ABK  
OR DG301ACK  
DG305AAK OR DG305ABK  
OR DG305ACK  
SEE PACKAGE 9  
DG301ACJ  
DG305ACJ  
SEE PACKAGE 7  
DG301AAL OR DG305AAL  
SEE PACKAGE 16

LOGIC	SW 1	SW 2
0	OFF	ON
1	ON	OFF

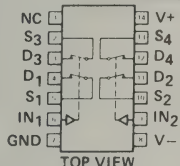


TOP VIEW

ORDER NUMBERS:  
DG301AAA OR DG301ABA  
DG305AAA OR DG305ABA  
SEE PACKAGE 2

## DUAL DPST DG302A or DG306A

Dual-In-Line and Flat Package



TOP VIEW

ORDER NUMBERS:  
DG302AAK OR DG302ABK  
OR DG302ACK  
DG306AAK OR DG306ABK  
OR DG306ACK  
SEE PACKAGE 9  
DG302ACJ  
DG306ACJ  
SEE PACKAGE 7  
DG302AAL OR DG306AAL  
SEE PACKAGE 16

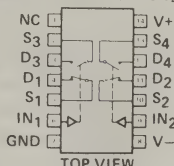
LOGIC	SWITCH
0	OFF
1	ON

## DUAL SPDT DG303A or DG307A

Dual-In-Line and Flat Package

LOGIC	SW 1	SW 2	SW 3	SW 4
0	OFF	ON	ON	OFF
1	ON	OFF	OFF	ON

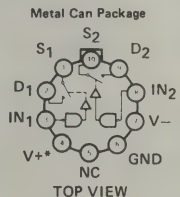
ORDER NUMBERS:  
DG303AAK OR DG303ABK  
OR DG303ACK  
DG307AAK OR DG307ABK  
OR DG307ACK  
SEE PACKAGE 9  
DG303ACJ  
DG307ACJ  
SEE PACKAGE 7  
DG303AAL OR DG307AAL  
SEE PACKAGE 16



TOP VIEW

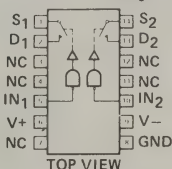
## DUAL SPST DG 381A

Dual-In-Line Package



TOP VIEW

ORDER NUMBERS:  
DG381AAK OR DG381ABK  
OR DG381ACK  
SEE PACKAGE 9  
DG381ACJ  
SEE PACKAGE 7



TOP VIEW

LOGIC	SW 1	SW 2
0	ON	OFF
1	OFF	ON

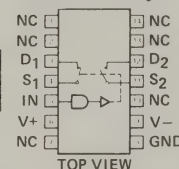
\*(SUBSTRATE AND CASE)

## SPDT DG387A

Dual-In-Line Package

LOGIC	SW 1	SW 2
0	OFF	ON
1	ON	OFF

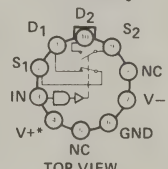
\*(SUBSTRATE AND CASE)



TOP VIEW

ORDER NUMBERS:  
DG387AAK OR DG387ABK  
OR DG387ACK  
SEE PACKAGE 9  
DG387ACJ  
SEE PACKAGE 7

Metal Can Package



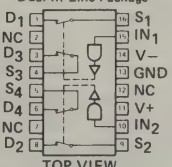
TOP VIEW

ORDER NUMBERS:  
DG387AAA OR DG387ABA  
SEE PACKAGE 2

## DUAL DPST DG384A

Dual-In-Line Package

ORDER NUMBERS:  
DG384AAK OR DG384ABK  
OR DG384ACK  
SEE PACKAGE 10  
DG384ACJ  
SEE PACKAGE 8



TOP VIEW

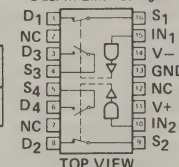
LOGIC	SW 1-4
0	OFF
1	ON

## DUAL SPDT DG390A

Dual-In-Line Package

LOGIC	SW 1	SW 2	SW 3	SW 4
0	OFF	ON	ON	OFF
1	ON	OFF	OFF	ON

ORDER NUMBERS:  
DG390AAK OR DG390ABK  
OR DG390ACK  
SEE PACKAGE 10  
DG390ACJ  
SEE PACKAGE 8



TOP VIEW

SWITCH STATES ARE FOR LOGIC "1" INPUTS (POSITIVE LOGIC)

DG300A-DG307A DG381A-DG390A

3

Analog Switches

# ABSOLUTE MAXIMUM RATINGS

Voltages referenced to V -

V +	44 V
GND	25 V
Digital inputs <sup>4</sup> , V <sub>S</sub> , V <sub>D</sub>	- 2 V to (V <sup>+</sup> + 2 V) or 30 mA, whichever occurs first
Current Any Terminal (Except S or D)	30 mA
Current, S or D, Continuous	30 mA
Pulsed 1 ms 10% Duty Cycle	100 mA
Operating Temperature (A Suffix)	- 55 to 125°C
(B Suffix)	- 20 to 85°C
(C Suffix)	0 to 70°C
Storage Temperature (A & B Suffix)	- 65 to 150°C
(C Suffix)	- 65 to 125°C

Power Dissipation\*

Cerchip (K)\*\* .....825 mW

Plastic DIP (J)***	470 mW
Metal Can (A)****	450 mW
Flat Package (L)*****	750 mW

\*Device mounted with all leads soldered or welded to PC board.

\*\*Derate 11 mW/°C above 75°C.

\*\*\*Derate 6.5 mW/°C above 25°C.

\*\*\*\*Derate 6 mW/°C above 75°C.

\*\*\*\*\*Derate 10 mW/°C above 75°C.

# ELECTRICAL CHARACTERISTICS

All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC			TYP <sup>1</sup> 25°C	MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V <sub>+</sub> = 15 V, V <sub>-</sub> = -15 V, GND = 0 V	
				A SUFFIX			B/C SUFFIX					
				-55°C/ -20°C	25°C	125°C/ 85°C	0°C	25°C	70°C			
1	V <sub>ANALOG</sub>	Minimum Analog Signal Handling Capability	± 15		± 15	± 15		± 15	± 15	V		
2	SWITCH	t <sub>DS(on)</sub> Drain Source ON Resistance	30	50	50	75	50	50	75	Ω	V <sub>D</sub> = + 10 V, I <sub>S</sub> = -10 mA	
3			30	50	50	75	50	50	75		V <sub>D</sub> = -10 V, I <sub>S</sub> = + 10 mA	
4		I <sub>S(off)</sub> Source OFF Leakage Current	0.1		1	100		5	100		V <sub>S</sub> = + 14 V, V <sub>D</sub> = -14 V	
5			-0.1		-1	-100		-5	-100		V <sub>S</sub> = -14 V, V <sub>D</sub> = + 14 V	
6		I <sub>D(off)</sub> Drain OFF Leakage Current	0.1		1	100		5	100	nA	V <sub>D</sub> = + 14 V, V <sub>S</sub> = -14 V	
7	H		-0.1		-1	-100		-5	-100		V <sub>D</sub> = -14 V, V <sub>S</sub> = + 14 V	
8		I <sub>D(on)</sub> Channel ON Leakage Current	0.1		1	100		5	100		V <sub>D</sub> = V <sub>S</sub> = + 14 V	
9			-0.1		-2	-200		-5	-200		V <sub>D</sub> = V <sub>S</sub> = -14 V	
10	INPUT	I <sub>INH</sub> Input Current	-0.001	-1	-1	-1		-1		μA	V <sub>IN</sub> = + 5.0 V	
11		Input Voltage High DG300A-307A Only	0.001	1	1	1		1			V <sub>IN</sub> = + 15 V	
12		I <sub>INL</sub> Input Current Input Voltage Low	-0.001	-1	-1	-1		-1			V <sub>IN</sub> = 0	
13	DYNAMIC	t <sub>on</sub> Turn-ON Time	150		300					ns	See Switching Time Test Circuit	
14		t <sub>off</sub> Turn-OFF Time	130		250							
15		t <sub>on</sub> Turn ON Time	110		250							
16		t <sub>off</sub> Turn OFF Time	70		150					ns	See Break-Before-Make Time Test Circuit	
17		t <sub>on</sub> -t <sub>off</sub> Break-Before-Make Interval	50									
18	ANALOG	Q Charge Injection	3							mV	R <sub>GEN</sub> = 0Ω, V <sub>GEN</sub> = 0V, C <sub>L</sub> = .01 μF	
19		C <sub>S(off)</sub> Source OFF Capacitance	14							pF	V <sub>S</sub> = 0, Note 2	
20		C <sub>D(off)</sub> Drain OFF Capacitance	14								V <sub>D</sub> = 0, Note 2	
21		C <sub>D(on)</sub> + C <sub>S(on)</sub> Channel ON Capacitance	40								V <sub>D</sub> = V <sub>S</sub> = 0, Note 2	
22			6								V <sub>IN</sub> = 0	
23	C <sub>IN</sub>	Input Capacitance	7							pF	V <sub>IN</sub> = + 15 V	
24												
25		OIRR OFF Isolation <sup>3</sup>	62							dB	V <sub>IN</sub> = 0, R <sub>L</sub> = 1 KΩ, V <sub>S</sub> = 1 V <sub>RMS</sub> , f = 500 KHz	
26	SUPPLY	CCRR Channel to Channel Crosstalk	74							mV	V <sub>IN</sub> = 4V (One Input) (All Other Inputs = 0)	
27		I <sub>+</sub> Positive Supply Current	0.23	1	0.5	0.5		1				
28		I <sub>-</sub> Negative Supply Current	-0.001	-10	-10	-100		-100				
29		I <sub>+</sub> Positive Supply Current	0.001	10	10	100		100				
30		I <sub>-</sub> Negative Supply Current	-0.001	-10	-10	-100		-100				
31	Y	I <sub>+</sub> Positive Supply Current	0.001	10	10	100		100		μA	V <sub>IN</sub> = 0.8 V (All Inputs)	
32		I <sub>-</sub> Negative Supply Current	-0.001	-10	-10	-100		-100			V <sub>IN</sub> = + 15V (All Inputs)	
33		I <sub>+</sub> Positive Supply Current	0.001	10	10	100		100			V <sub>IN</sub> = 0 (All Inputs)	

## NOTES:

1. Typical values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

2. V<sub>IN</sub> = input voltage to perform proper function,

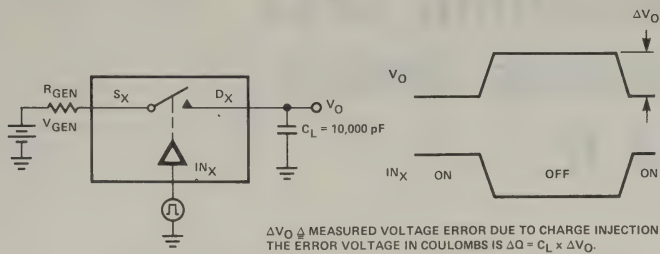
DG300A-303A: DG381A-390A: V<sub>IN</sub> = For logic "1" = 4 V, for logic "0" = 0.8V

DG304A-307A: V<sub>IN</sub> = For logic "1" = 11 V, for logic "0" = 3.5 V

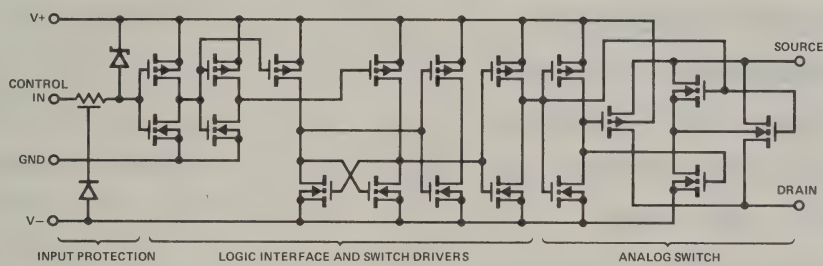
3. "OFF" isolation = 20 log V<sub>S</sub>/V<sub>D</sub>, V<sub>S</sub> = input to OFF switch, V<sub>D</sub> = Output

4. Signals on S<sub>X</sub>, D<sub>X</sub> or I<sub>NX</sub> exceeding V<sub>+</sub> or V<sub>-</sub> will be clamped by internal diodes. Limit forward diode current to maximum current ratings.

DG381A ICMJ-C	DG300A ICMJ-A	DG302A ICMJ-A
DG384A ICMJ-A	DG301A ICMJ-B	DG303A ICMJ-C
DG387A ICMJ-B	DG304A ICMJ-D	DG306A ICMJ-D
DG390A ICMJ-C	DG305A ICMJ-E	DG307A ICMJ-F

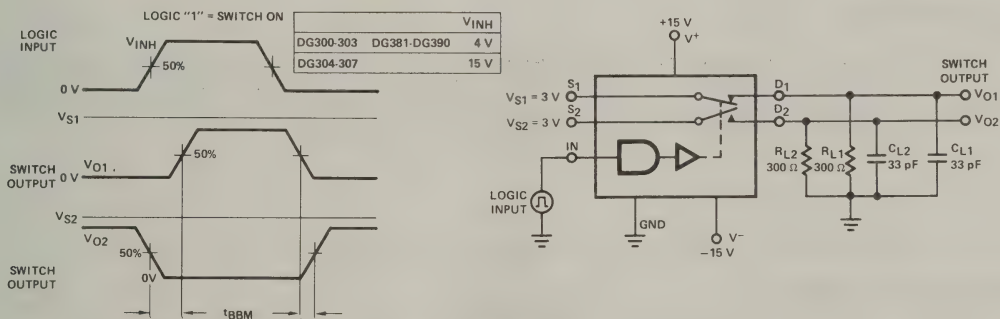


SCHEMATIC OF TYPICAL SWITCH

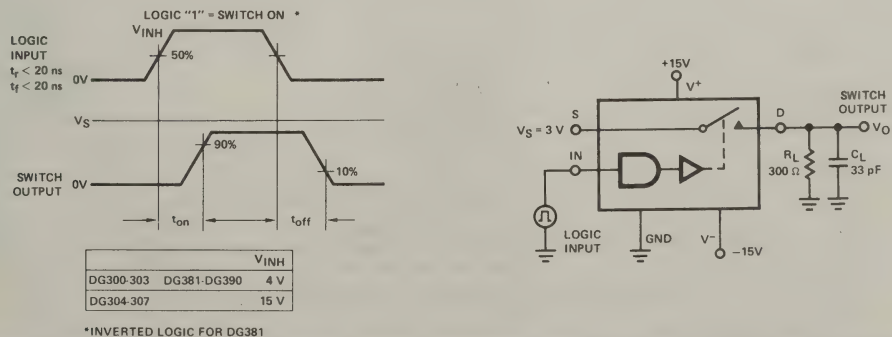


TEST CIRCUITS

BREAK-BEFORE-MAKE TIME TEST CIRCUIT SPDT  
(DG301A, DG303A, DG305A, DG307A, DG384A, DG390A)



SWITCHING TIME TEST CIRCUITS (DG300A-307A, DG381A-390A)



# Quad Monolithic SPST CMOS Analog Switch *designed for...*



- Portable, Battery Instrumentation
- Automotive Applications
- Computer Peripherals
- Communication Systems
- High Speed Multiplexing
- Low Leakage Switching
- Sample and Hold
- Data Acquisition Systems

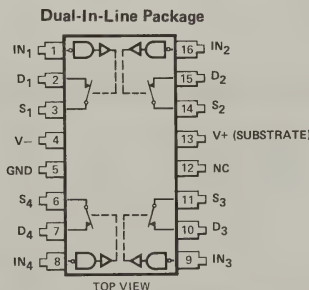
## BENEFITS

- High Speed Switching with Break-Before-Make
  - $t_{ON} = 130$  nsec Typical
  - $t_{OFF} = 90$  nsec Typical
- Single Supply Operation
  - +5 V to +30 V
- CMOS Compatible (positive logic)
- Wide Signal Range  $\pm 15$  V
- Low Standby Power
  - $< 30$   $\mu$ Watt Typical
- Minimizes Signal Error
  - $r_{DS} < 80 \Omega$  Typical
  - $I_{D(off)} < 100$  pA Typical
- Environmentally Rugged
  - Latchproof CMOS Process

## DESCRIPTION

The DG308 is a monolithic quad single-pole single-throw analog switch fabricated in complementary MOS technology. In the ON condition, each switch will conduct current in either direction and in the OFF condition each switch will block voltages up to 30 volts peak to peak. The ON-OFF State of each switch is controlled by a driver. With CMOS logic '1' at the input the switch will be ON, with logic '0' at the input the switch will be OFF.

## PIN CONFIGURATION



ORDER NUMBER:  
DG308CJ  
SEE PACKAGE 7

LOGIC	SWITCH
0	OFF
1	ON

SWITCH CLOSED FOR LOGIC "1" INPUT (POSITIVE LOGIC)



# ABSOLUTE MAXIMUM RATING

$V_{IN}$ to Ground .....	$V^+ + 18\text{ V}, V^+ - 36\text{ V}$
$V_S$ or $V_D$ .....	$V^+$ to $V^-$
$V^+$ to Ground .....	+36 V
$V^+$ to $V^-$ .....	+36 V
Current, Any Terminal (Except S or D) .....	30 mA
Current, S or D, Continuous .....	20 mA
Pulsed 1 ms 10% Duty Cycle .....	100 mA
Operating Temperature (C Suffix) .....	0 to +70°C

Storage Temperature (C Suffix) .....	-65 to +125°C
Power Dissipation (Package)* .....	
16 Pin Plastic DIP** .....	470 mW

\*Device mounted with all leads soldered or welded to PC board.

\*\*Derate 6.5 mW/°C above 25°C.

# ELECTRICAL CHARACTERISTICS

All DC parameters are 100% tested at 25°C. Lots are sample tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC		(Note 1) TYP 25°C	MAX LIMITS C SUFFIX			UNIT	TEST CONDITIONS $V^+ = +15\text{ V}$ $V^- = -15\text{ V}, \text{Gnd} = 0\text{ V}$	
			0°C	25°C	70°C			
1	Minimum Analog $V_{ANALOG}$ Signal Handling Capability	$\pm 15$		$\pm 15$	$\pm 15$	V	Switch ON $I_S = 10\text{ mA}$	
2	S W I T C H  I N P U T  D Y N A M I C  S U P	$r_{DS(ON)}$ Drain Source ON Resistance	70	100	100	125	$V_D = 10\text{ V}, I_S = -1\text{ mA}$	(Note 2)
3			60	100	100	125	$V_D = -10\text{ V}, I_S = 1\text{ mA}$	
4		$I_{S(off)}$ Source OFF Leakage Current	0.1		5	100	$V_S = +14\text{ V}, V_D = -14\text{ V}$	(Note 2)
5			-0.1		-5	-100	$V_S = -14\text{ V}, V_D = +14\text{ V}$	
6		$I_{D(off)}$ Drain OFF Leakage Current	0.1		5	100	$V_S = -14\text{ V}, V_D = +14\text{ V}$	
7			-0.1		-5	-100	$V_S = +14\text{ V}, V_D = -14\text{ V}$	(Note 2)
8		$I_{D(on)}$ Drain ON Leakage Current	0.1		5	200	$V_D = V_S = +14\text{ V}$	
9			-0.1		-5	-200	$V_D = V_S = -14\text{ V}$	
10		$I_{INH}$ Input Current Input Voltage High	0.001		1		$V_{IN} = 15\text{ V}$	
11		$I_{INL}$ Input Current Input Voltage Low	-0.001		-1		$V_{IN} = 0\text{ V}$	
12	D Y N A M I C	$t_{on}$ Turn-ON Time	130		200		See Switching Time Test Circuit	
13		$t_{off}$ Turn-OFF Time	90		150			
14		$C_{S(off)}$ Source OFF Capacitance	8				$V_S = 0\text{ V}, V_{IN} = 0\text{ V}$	
15		$C_{D(off)}$ Drain OFF Capacitance	8				$V_D = 0\text{ V}, V_{IN} = 0\text{ V}$	
16		$C_{D(on)+C_{S(on)}}$ Channel ON Capacitance	22				$V_D = V_S = 0\text{ V}, V_{IN} = 15\text{ V}$	
17		OFF Isolation (Note 3)	78				$V_{IN} = 0\text{ V}, R_L = 1\text{ K } \Omega, C_L = 3\text{ pF}$ $V_S = 70\text{ mV rms}, f = 500\text{ kHz}$	
18	S U P	$I^+$ Positive Supply Current	0.001		100		$V_{IN} = 15\text{ V or } 0\text{ V}$	
19		$I^-$ Negative Supply Current	-0.001		-100			

## NOTES:

- Typical values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.
- $V_{IN}$  = Input Voltage to perform proper function for logic '1' = 11V, for logic '0' = 3.5V

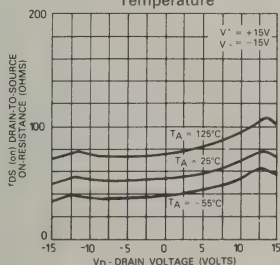
$$3. \text{ OFF Isolation} = 20 \log_{10} \frac{|V_D|}{|V_S|}$$

$V_D$  = Output  
 $V_S$  = Input to OFF Switch

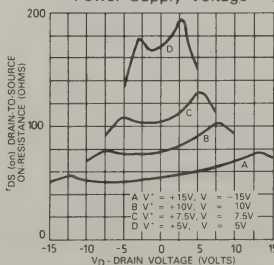
ICMD

## TYPICAL CHARACTERISTICS

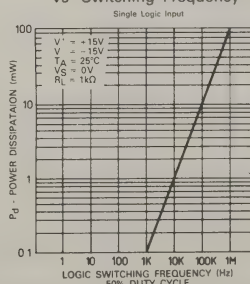
$r_{DS(ON)}$  vs  $V_D$  and Temperature



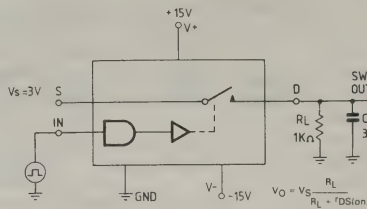
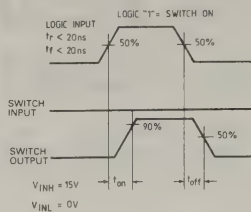
$r_{DS(ON)}$  vs  $V_D$  and Power Supply Voltage



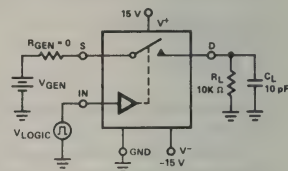
Device Power Dissipation vs Switching Frequency



# SWITCHING TIME TEST CIRCUIT



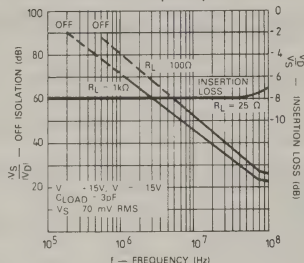
Typical delay, rise, fall, settling times, and switching transients in this circuit.



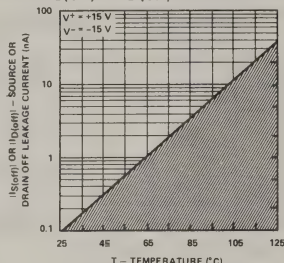
If  $R_{GEN}$ ,  $R_L$  or  $C_L$  is increased, there will be proportional increases in rise and/or fall RC times. Applying  $V_{GEN}$  to D rather than S results in much greater spikes.

## TYPICAL CHARACTERISTICS continued

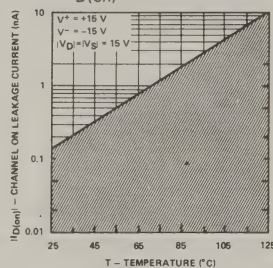
OFF-Isolation, Insertion Loss vs Frequency



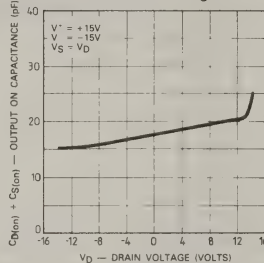
$I_S(off)$  or  $I_D(off)$  vs Temperature\*



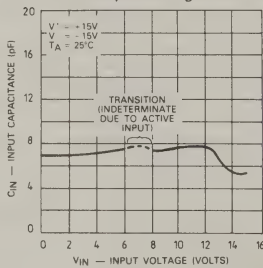
$I_D(on)$  vs Temperature\*



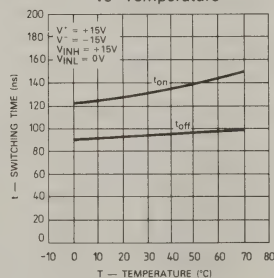
Output ON Capacitance vs Drain Voltage



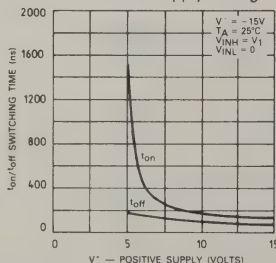
Input Capacitance vs Input Voltage



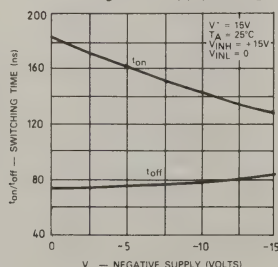
Switching Time vs Temperature



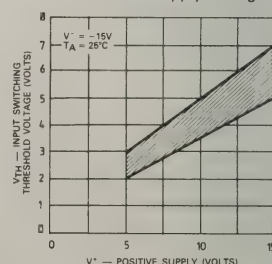
Switching Time vs Positive Supply Voltage



Switching Time vs Negative Supply Voltage



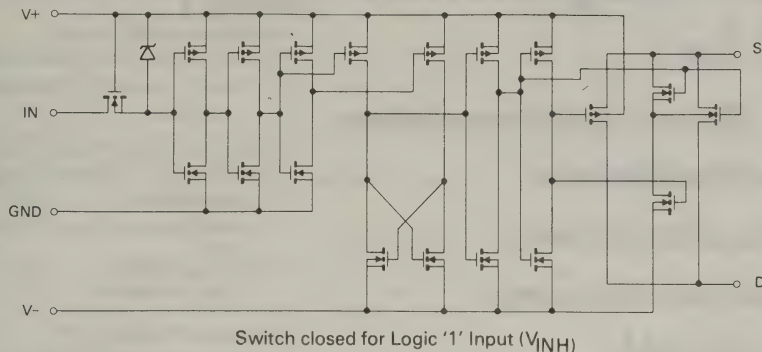
Input Switching Threshold vs Positive Supply Voltage



\*Note: the turn-off time is primarily limited here by the RC time constant (100ns) of the load.

\*The net leakage into the source or drain is the n-channel leakage minus the p-channel leakage. This difference can be positive, negative, or zero depending on the analog voltage and temperature, and will vary greatly from unit to unit.

## PARTIAL SCHEMATIC OF TYPICAL SWITCH

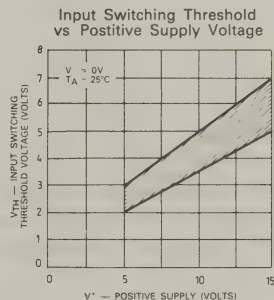
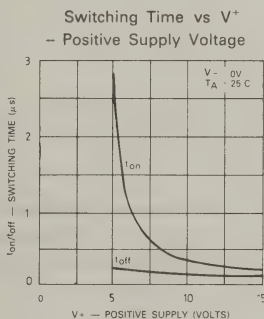
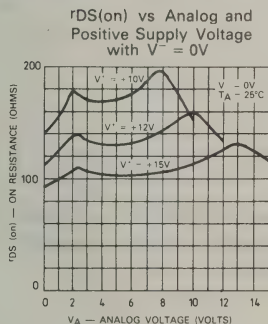


## Single Supply Operation

The DG308 will switch positive analog signals while using a single positive supply. This will allow use in many applications where only one supply is available. The performance trade-offs while using single supplies are: 1) Increased  $r_{DS(ON)}$ ; 2) slower switching speed. Typical curves for aid in designing with single supplies are supplied in the Figures below. As stated in the absolute maximum ratings section of the data sheet, the analog voltage should not go above or below the supply voltages which in single operation are  $V+$  and 0 volts.

**Single Supply Range:** ( $V-$  and GND Tied Together)  $V+:$  +5 V to +25 V

**Analog Signal Range:**  $V- \leq V_{ANALOG} \leq V+$



# Quad Monolithic SPST CMOS Analog Switch

*designed for . . .*

- Portable, Battery Instrumentation
- Computer Peripherals
- Communication Systems
- High Speed Multiplexing
- Sample and Hold
- Single or Dual Supply Systems

## BENEFITS

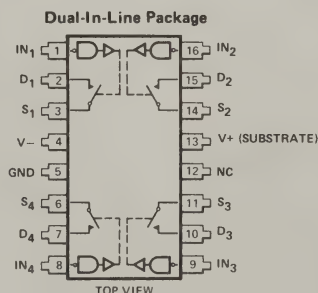
- **Environmentally Rugged**
  - 40 V Power Supply Max Rating
  - Static Protected Logic Inputs
  - Latchproof
- **Minimizes System Power Requirements**
  - Operates Off Single Supply When  $V_-$  Tied to GND
  - Low Quiescent Power  $< 30 \mu\text{W}$  Typ
- **Fast**  $t_{\text{on}} < 200 \text{ ns}$   
 $t_{\text{off}} < 150 \text{ ns}$
- **Minimizes Signal Error**
  - $r_{\text{DS(ON)}} < 100 \Omega$
  - $I_{\text{D(OFF)}} < 5 \text{ nA}$
  - Full Rail-to-Rail Analog Signal Range
- **Easily Interfaced**
  - CMOS Logic Compatible
  - Available in Normally Open or Normally Closed
- **DG201A/DG202 are TTL Input Pin-for-Pin Compatible**

## DESCRIPTION:

The DG309 designed on the Siliconix PLUS-40 CMOS process provides solid state switch action with 100 ohms contact (ON) resistance and very high OFF resistance. True bidirectional switch action occurs over the full analog signal range of  $\pm 15 \text{ V}$ , with Break-Before-Make operation to prevent momentary shorting of signal inputs.

## PIN CONFIGURATION

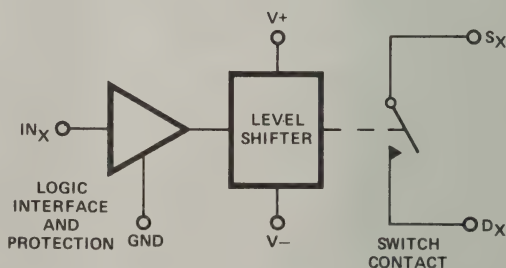
LOGIC	SWITCH
0	ON
1	OFF



ORDER NUMBER:  
DG309CJ  
See Package 8

SWITCHES ARE SHOWN IN THE LOGIC "1" INPUT STATE

## FUNCTIONAL DIAGRAM (typical switch)





# ABSOLUTE MAXIMUM RATINGS

Voltages referenced to V-

V+ ..... 44 V

GND ..... 25 V

Digital inputs<sup>4</sup>, V<sub>S</sub>, V<sub>D</sub> : -2 V to (V<sup>+</sup>+2 V) or 20 mA, whichever occurs first.

Current, Any Terminal

(Except S or D) ..... 30 mA

Current, S or D, Continuous ..... 20 mA

Pulsed 1 ms 10% Duty Cycle ..... 100 mA

Operating Temperature

(C Suffix) ..... 0 to +70°C

Storage Temperature

(C Suffix) ..... -65 to +125°C

Power Dissipation (Package)\*

16 Pin Plastic DIP\*\* ..... 470 mW

\*Device mounted with all leads soldered or welded to PC board.

\*\*Derate 6.5 mW/°C above 25°C.

# ELECTRICAL CHARACTERISTICS

All DC parameters are 100% tested at 25°C. Lots are sample tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC			(Note 1) TYP 25°C	MAX LIMITS C SUFFIX			UNIT	TEST CONDITIONS V+ = +15 V V- = -15 V, Gnd = 0 V		
				0°C	25°C	70°C				
1	SWITCH	V <sub>ANALOG</sub> Minimum Analog Signal Handling Capability	±15		±15	±15	V			
2		r <sub>DS(ON)</sub> Drain Source ON Resistance	70	100	100	125	Ω	V <sub>D</sub> = 10 V, I <sub>S</sub> = -1 mA	(Note 2)	
3			60	100	100	125		V <sub>D</sub> = -10 V, I <sub>S</sub> = 1 mA		
4		I <sub>S(off)</sub> Source OFF Leakage Current	0.1		5	100	nA	V <sub>S</sub> = +14 V, V <sub>D</sub> = -14 V	(Note 2)	
5			-0.1		-5	-100		V <sub>S</sub> = -14 V, V <sub>D</sub> = +14 V		
6		I <sub>D(off)</sub> Drain OFF Leakage Current	0.1		5	100		V <sub>S</sub> = -14V, V <sub>D</sub> = +14 V		
7			-0.1		-5	-100		V <sub>S</sub> = +14V V <sub>D</sub> = -14 V		
8		I <sub>D(on)</sub> Drain ON Leakage Current	0.1		5	200		V <sub>D</sub> = V <sub>S</sub> = + 14 V	(Note 2)	
9	-0.1			-5	-200	V <sub>D</sub> = V <sub>S</sub> = - 14 V				
10	INPUT	I <sub>INH</sub> Input Current Input Voltage High	0.001		1		μA	V <sub>IN</sub> = 15 V		
11		I <sub>INL</sub> Input Current Input Voltage Low	-0.001		-1			V <sub>IN</sub> = 0 V		
12	DYNAMIC	t <sub>on</sub> Turn-ON Time	130		200		ns	See Switching Time Test Circuit		
13		t <sub>off</sub> Turn-OFF Time	90		150					
14		C <sub>S(off)</sub> Source OFF Capacitance	8				pF	V <sub>S</sub> = 0 V, V <sub>IN</sub> = 15 V		
15		C <sub>D(off)</sub> Drain OFF Capacitance	8					V <sub>D</sub> = 0 V, V <sub>IN</sub> = 15 V		
16		C <sub>D(on)+CS(on)</sub> Channel ON Capacitance	22					V <sub>D</sub> =V <sub>S</sub> = 0 V, V <sub>IN</sub> = 0 V		
17			OFF Isolation (Note 3)	78				dB	V <sub>IN</sub> =15 V, R <sub>L</sub> =1K Ω, C <sub>L</sub> = 3 pF V <sub>S</sub> = 70m V rms, f = 500 kHz	
18	SUP	I+ Positive Supply Current	0.001		100		μA	V <sub>IN</sub> = 15 V or 0 V		
19		I- Negative Supply Current	-0.001		-100					

## NOTES:

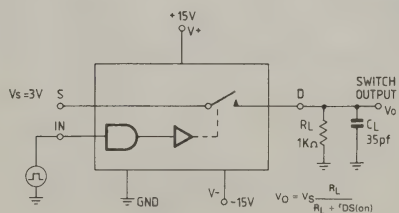
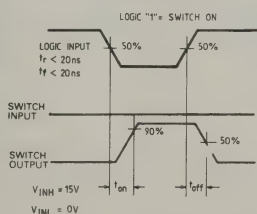
1. Typical values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

2. V<sub>IN</sub> = Input Voltage to perform proper function for logic '1' = 11V, for logic '0' = 3.5V

3. OFF Isolation = 20 log<sub>10</sub>  $\frac{|V_D|}{|V_S|}$  V<sub>D</sub> = Output  
V<sub>S</sub> = Input to OFF Switch ICMF-B

4. Signals on S<sub>X</sub>, D<sub>X</sub> or IN<sub>X</sub> exceeding V<sup>+</sup> or V<sup>-</sup> will be clamped by internal diodes. Limit forward diode current to maximum current ratings.

## SWITCHING TIME TEST CIRCUIT



# Monolithic General Purpose CMOS Analog Switches

*designed for . . .*



- Programmable Gain Amplifiers
- Analog Multiplexing
- Servo Control Switching
- Sampled Data Systems
- Synchronous Demodulators

## BENEFITS

- Environmentally Rugged
  - 44V Power Supply Rating
  - Static Protected Logic Inputs
  - Latchproof
- Easily Interfaced
  - TTL and CMOS Compatible without Pull Up Resistors
- Reduces External Component Requirements
  - Full Rail to Rail Analog Signal Range
  - No Diode Protection Required Between  $V_L$  and  $V+$  for Power Supply Sequencing
- Pin for Pin Compatible with
  - IH5040 Family
  - HI5040 Family

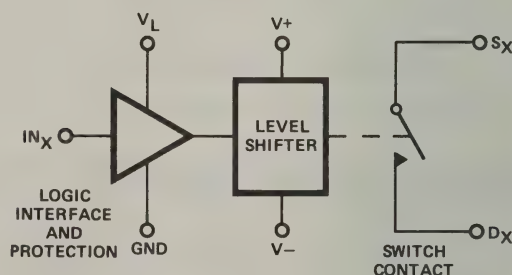
## DESCRIPTION

The DG5040 through DG4045 series designed on the Siliconix PLUS-40 CMOS process provides solid state switch action with 50 ohms contact resistance and very high OFF resistance. True switch action takes place over the full analog signal range of  $\pm 15$  volts, with Break-Before-Make operation to prevent momentary shorting of signal inputs.

## FUNCTIONAL DESCRIPTION

PART NUMBER	TYPE	
DG5040		SPST
DG5041	Dual	SPST
DG5042		SPDT
DG5043	Dual	SPDT
DG5044		DPST
DG5045	Dual	DPST

## FUNCTIONAL DIAGRAM (typical channel)



# PIN CONFIGURATIONS

ALL SWITCHES SHOWN IN  
THE LOGIC "1"  
SWITCH STATE

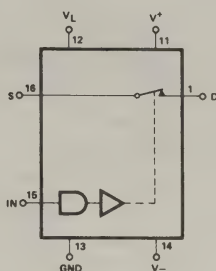
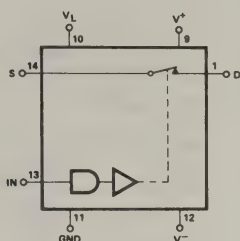
FLAT PACK (L)  
SEE PACKAGE 5

CERDIP (K) OR  
PLASTIC (J)  
SEE PACKAGE 8 or 10

METAL CAN (A)  
SEE PACKAGE 2

SPST  
DG5040

LOGIC	SWITCH
0	OFF
1	ON



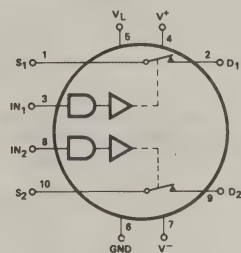
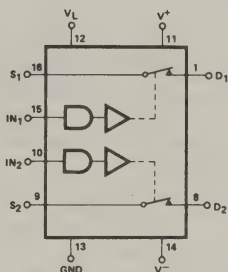
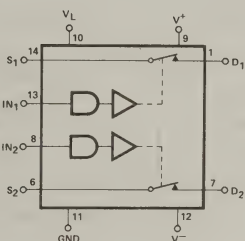
ORDER  
NUMBER:

DG5040AL

DG5040AK or DG5040CK  
or DG5040CJ

DUAL SPST  
DG5041

LOGIC	SWITCH
0	OFF
1	ON



ORDER  
NUMBER:

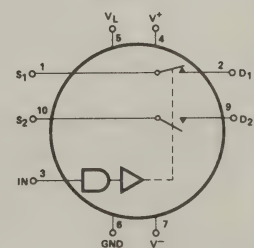
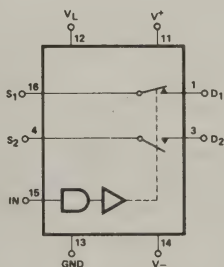
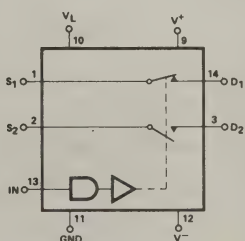
DG5041AL

DG5041AK or DG5041CK  
or DG5041CJ

DG5041AA

SPDT  
DG5042

LOGIC	SW 1	SW 2
0	OFF	ON
1	ON	OFF



ORDER  
NUMBER:

DG5042AL

DG5042AK or DG5042CK  
or DG5042CJ

DG5042AA

**PIN CONFIGURATIONS** Continued

ALL SWITCHES SHOWN IN  
THE LOGIC "1"  
SWITCH STATE

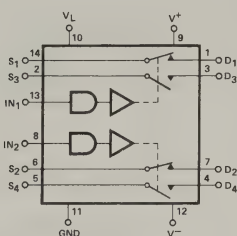
FLAT PACK (L)  
SEE PACKAGE 5

CERDIP (K) OR  
PLASTIC (J)  
SEE PACKAGE 8 or 10

METAL CAN (A)  
SEE PACKAGE 2

DUAL SPDT  
DG5043

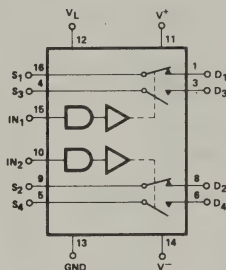
LOGIC	SW 1 SW 2	SW 3 SW 4
0	OFF	ON
1	ON	OFF



ORDER  
NUMBER:

DG5043AL

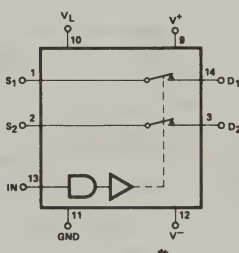
(DG191 EQUIVALENT)



DG5043AK or DG5043CK  
or DG5043CJ

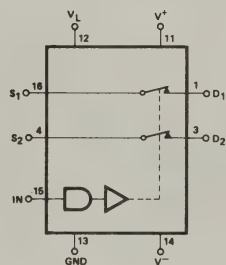
DPST  
DG5044

LOGIC	SWITCH
0	OFF
1	ON

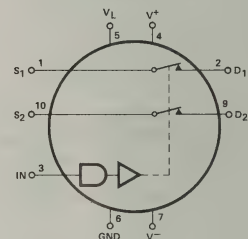


ORDER  
NUMBER:

DG5044AL



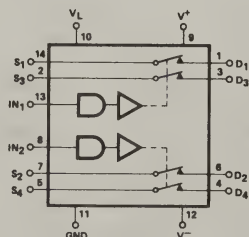
DG5044AK or DG5044CK  
or DG5044CJ



DG5044AA

DUAL DPST  
DG5045

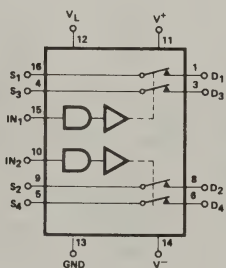
LOGIC	SWITCH
0	OFF
1	ON



ORDER  
NUMBER:

DG5045AL

(DG185 EQUIVALENT)



DG5045AK or DG5045CK  
or DG5045CJ



# ABSOLUTE MAXIMUM RATINGS (T<sub>A</sub> = 25° unless otherwise noted)

Voltages referenced to V-	
V+ .....	44 V
V <sub>L</sub> .....	(GND -0.3 V) to 44 V
GND .....	25 V
Digital inputs <sup>5</sup> , V <sub>S</sub> , V <sub>D</sub> .....	-2 V to (V <sup>+</sup> +2 V) or 30 mA, whichever occurs first.
Current, Any Terminal Except S or D .....	30 mA
Continuous Current, S or D .....	30 mA
Peak Current, S or D (pulsed at 1 msec, 10% duty cycle max) .....	100 mA
Storage Temperature (A Suffix) .....	-65 to 150°C
(C Suffix) .....	-65 to 125°C

Operating Temperature (A Suffix) .....	-55 to 125°C
(C Suffix) .....	0 to 70°C
Power Dissipation*	
Metal Can and Plastic DIP** .....	450 mW
16 Pin DIP**** .....	900 mW
Flat Pak***** .....	900 mW

\*All leads welded or soldered to PC board.

\*\*Derate 6 mW/°C above 75°C.

\*\*\*\*Derate 12 mW/°C above 75°C.

\*\*\*\*\*Derate 10 mW/°C above 75°C.

**ELECTRICAL CHARACTERISTICS** All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

Characteristics			Max Limits						Unit	Test Conditions V+ = 15V, V- = -15V VL = 5V, GND = 0V				
			A Suffix			C Suffix								
			-55°C	25°C	125°C	0°C	25°C	70°C						
1	SWITCH	VANALOG	Min. Analog Signal Handling Capability		±15	±15		±15	±15	V				
2		rDS(on) <sup>3</sup>	Drain Source ON Resistance	50	50	75	50	50	75	Ω	VD = 10V, IS = -10 mA	Note 1		
3			50	50	75	50	50	75	VD = -10V, IS = -10 mA					
4		IS(off) <sup>3</sup>	Source OFF Leakage Current		1	100		1	100	nA	VS = 14V, VD = -14V		Note 1	
5				-1	-100		-1	-100	VS = -14V, VD = 14V					
6		ID(off) <sup>3</sup>	Drain OFF Leakage Current		1	100		1	100		VS = -14V, VD = 14V			
7				-1	-100		-1	-100	VS = 14V, VD = -14V					
8		ID(on) <sup>3</sup>	Drain ON Leakage Current		2	200		2	200		VS = VD = 14V			
9			-2	-200		-2	-200	VS = VD = -14V						
10	INPUT	IINH <sup>3</sup>	Input Current, Input Voltage High		±1	±1		±1	±1	μA	VINH = 2.0V	Note 2		
11		IINL <sup>3</sup>	Input Current, Input Voltage Low		±1	±1		±1	±1		VINL = 0.8V			
12	DYNAMIC	ton <sup>4</sup>	Turn-ON Time		1000			1200		ns	VS = ±10V, RL = 1KΩ, CL = 35 pF		Note 2	
13		toff <sup>4</sup>	Turn-OFF Time		500			700						
14		Q	Charge Injection	3 Typical						mV	CL = 10,000 pF, RGEN = 0Ω, VGEN = 0V			
15			CS(off)	Source OFF Capacitance	15 Typical						pF			VS = VD = 0V, f = 1 MHz
16			CD(off)	Drain OFF Capacitance	17 Typical									
17	CD(on) + CS(on)		Channel ON Capacitance	45 Typical										
18	OIRR		OFF Isolation	75 Typical						dB				
19	CCRR	Interchannel Crosstalk Isolation	89 Typical											
20	SUPPLY	I+ <sup>3</sup>	Positive Supply Current	300	300	300	300	300	300	μA	VIN = 0V or 2.4V			
21		I- <sup>3</sup>	Negative Supply Current	-300	-300	-300	-300	-300	-300					
22		IL <sup>3</sup>	Logic Supply Current	300	300	300	300	300	300					
23		IGND	Ground Current	-300	-300	-300	-300	-300	-300					

ICMK-A, B

## NOTES:

- V<sub>IN</sub> = Input voltage to perform proper function.  
For Logic "1" — V<sub>INH</sub> = 2.0 V  
For Logic "0" — V<sub>INL</sub> = 0.8 V

- See Switching Time Test Circuit.

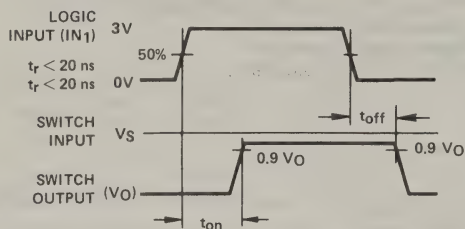
- Limits of these parameters are tested 100% at 25 °C and 125°C for "/883" devices.

- For "/883" devices these parameters are 100% tested at 25°C.

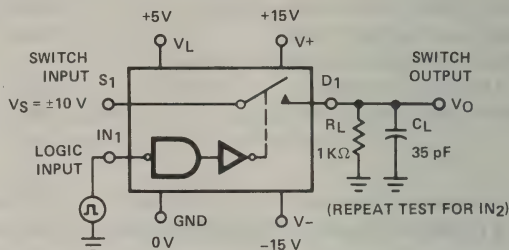
- Signals on S<sub>X</sub>, D<sub>X</sub> or I<sub>NX</sub> exceeding V<sup>+</sup> or V<sup>-</sup> will be clamped by internal diodes. Limit forward diode current to maximum current ratings.

## SWITCHING TIME TEST CIRCUIT

Switch output waveform shown for  $V_S = \text{constant}$  with logic input waveform as shown. Note that  $V_S$  may be + or – as per switching time test circuit.  $V_O$  is the steady state output with switch on. Feedthrough via gate capacitance may result in spikes at leading and trailing edge of output waveform.

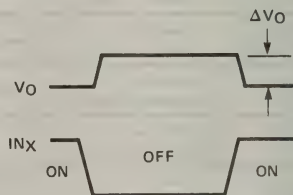
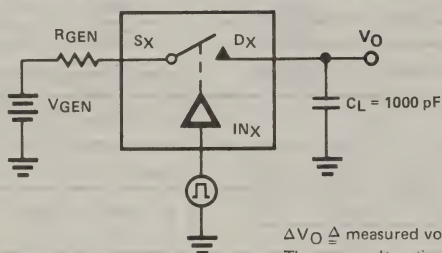


**Note:** Logic input waveform is inverted for switches that have the opposite logic sense control.



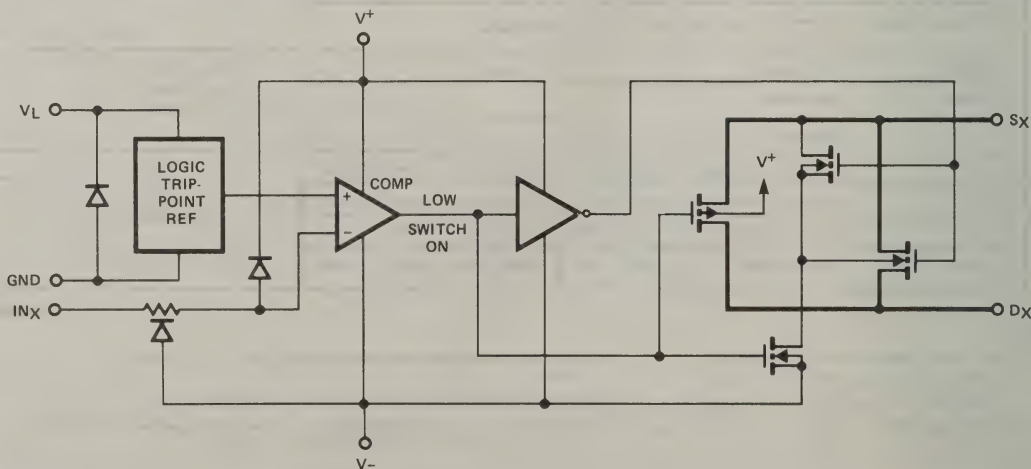
$$V_O = V_S \frac{R_L}{R_L + r_{DS(on)}}$$

## CHARGE INJECTION TEST CIRCUIT



$\Delta V_O \triangleq$  measured voltage error due to charge injection.  
The error voltage in coulombs is  $\Delta Q = C_L \times \Delta V_O$ .

## SCHEMATIC DIAGRAM (typical channel)



# Monolithic SPST MOS Switch with Driver



Si3002

*designed for . . .*

## ■ Switching Analog Signals such as Reference Signals

### BENEFITS

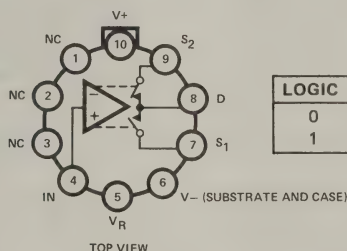
- Reduces External Component Requirements
  - Internal Zener Diodes Protect All MOS Gates
- Easily Interfaced
  - TTL and DTL Integrated Logic

### DESCRIPTION

The Si3002 contains two P-channel MOS field-effect transistors designed to function as single-pole double-throw electronic switches. A level-shifting driver enables a low-level input (0.8 to 2 V) to control the ON-OFF state of the switches. In the ON state, each switch will conduct current equally well in either direction. In the OFF state the switches will block voltages up to 20 V peak-to-peak. With logic "0" at the driver input, a common drain (D) is connected through an ON switch to source ( $S_1$ ). With logic "1" at the input, "D" is connected to  $S_2$ . Switch action is make-before-break.

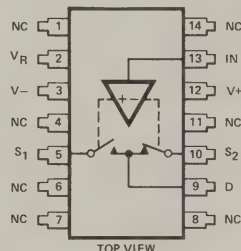
### PIN CONFIGURATIONS

Metal Can Package



ORDER NUMBER: Si3002AA  
SEE PACKAGE 2

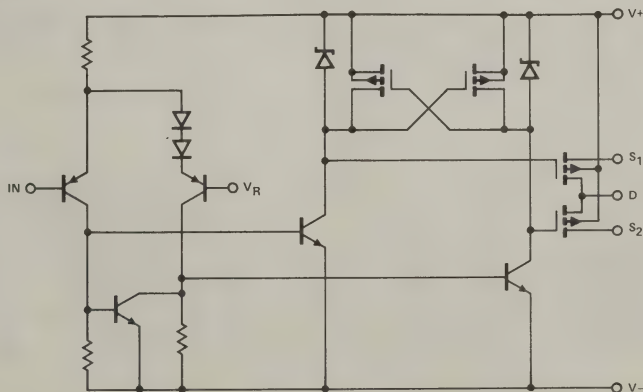
Dual-In-Line Package



ORDER NUMBER: Si3002BP  
SEE PACKAGE 11

LOGIC STATES ARE FOR LOGIC "1" INPUT  
(POSITIVE LOGIC)

### SCHEMATIC DIAGRAM



## ABSOLUTE MAXIMUM RATINGS

$V^+$ to $V^-$ .....	36 V
$V^+$ to $V_S$ or $V_D$ .....	25 V
$V^+$ to $V_R$ or $V_{IN}$ .....	12 V
$V_D$ to $V^-$ .....	36 V
$V_S$ to $V^-$ .....	36 V
$V_D$ to $V_S$ .....	$\pm 25$ V
$V_{IN}$ to $V_R$ .....	$\pm 6$ V
Current (Any Terminal) .....	30 mA
Storage Temperature .....	-65 to 150°C

Operating Temperature (A Suffix) ..... -55 to 125°C  
 (B Suffix) ..... -20 to 85°C

Power Dissipation \*

Metal Can\*\* ..... 450 mW

14 Pin DIP\*\*\* ..... 825 mW

\* Device mounted with all leads soldered or welded to PC board.

\*\* Derate 6 mW/°C above 75°C.

\*\*\* Derate 11 mW/°C above 75°C.

## ELECTRICAL CHARACTERISTICS

All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

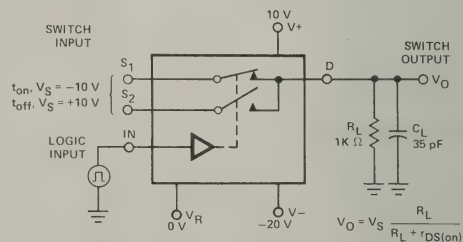
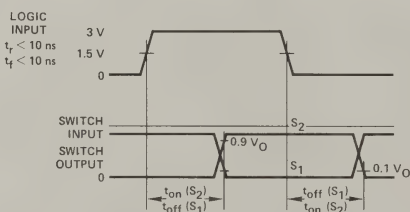
CHARACTERISTIC			MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V+ = 10 V, V- = -20 V, VR = 0			
			A SUFFIX			B SUFFIX							
			-55°C	25°C	125°C	-20°C	25°C	85°C					
1	SWITCH	rDS(on) Drain-Source ON Resistance	100	100	150	100	100	150	Ω	VD = 10 V	IS = -1 mA	VINL = 0.8 V (Sw1 ON) VINH = 2.0 V (Sw2 ON)	
2			150	150	250	150	150	250		VD = 0			
3			400	400	500	400	400	500		VD = -10 V			
4		IS(off) Source OFF Leakage Current	-1	-1000	-	-5	-100	nA	VS = -10 V, VD = 10 V				
5	ID(on) + IS(on) Channel ON Leakage Current	-2	-2000		-10	-200	VD = -10 V, IS = 0						
6	INPUT	IINL Input Current, Input Voltage Low	-1.0	-0.8	-0.8	-1.0	-0.8	-0.8	mA	VIN = 0 (Sw1 ON)			
7		IINH Input Current, Input Voltage High	0.1	0.1	10	0.1	0.1	10		μA			VIN = 5.5 V (Sw2 ON)
8	DELAY	ton Turn-ON Time		1.0			1.0		μs	See Switching Time Test Circuit			
9		toff Turn-OFF Time		1.5			1.5						
10		CS(off) Source OFF Capacitance		6 Typ*			6 Typ*					VS = 0	f = 1 MHz
11	SUPPLY	I+ Positive Supply Current		3			3.5		mA	VIN = 0			
12		I- Negative Supply Current		-3			-3						
13		IR Reference Supply Current		-0.1			-0.1						
14		I+ Positive Supply Current		3			3.5		mA	VIN = 5 V			
15		I- Negative Supply Current		-3			-3						
16		IR Reference Supply Current		-1.5			-1.5						

\*Typical values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

CMBC

## SWITCHING TIME TEST CIRCUIT

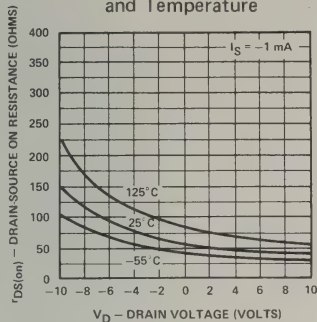
Switch output waveform shown for  $V_S =$  constant with logic input waveform as shown. Note that  $V_S$  may be + or - as per switching time test circuit.  $V_O$  is the steady state output with switch on. Feedthrough via gate capacitance may result in spikes at leading and trailing edge of output waveform.



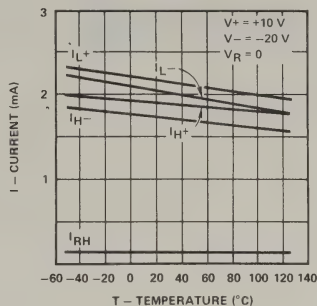


# TYPICAL CHARACTERISTICS

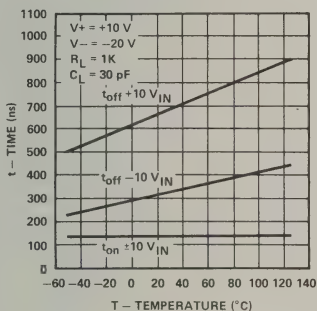
$r_{DS(on)}$  vs  $V_D$  and Temperature



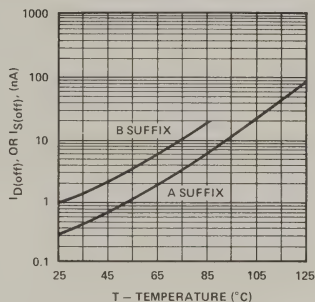
Supply Current vs Temperature



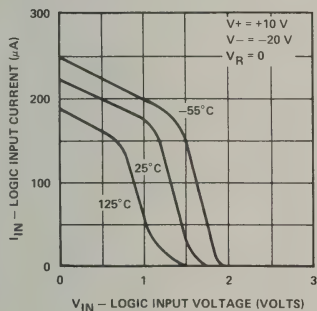
Switching Time vs Temperature



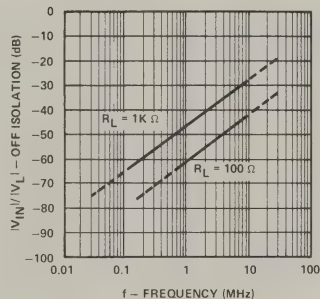
$I_{S(off)}$  vs Temperature



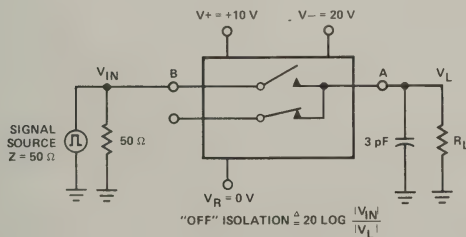
$V_{IN}$  vs  $I_{IN}$  and Temperature



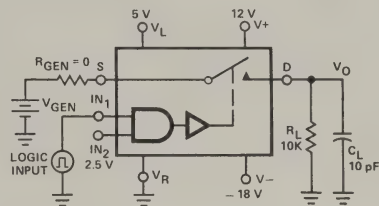
"OFF" Isolation vs  $R_L$  and Frequency



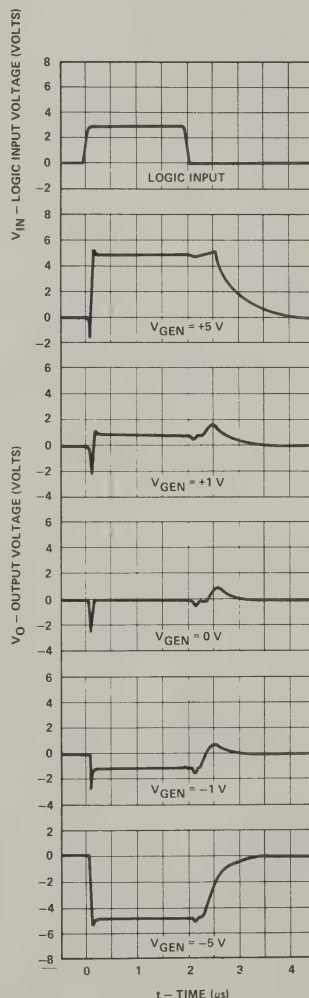
"OFF" Isolation Circuit



Typical delay, rise, fall, settling times, and switching transients in this circuit.



If  $R_{GEN}$ ,  $R_L$  or  $C_L$  is increased, there will be proportional increases in rise and/or fall RC times.



SI3002

3 Analog Switches





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Linear	6
A/D Converters	7
D/A Converters	8
Die Process & Topography	9
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Appendices	12

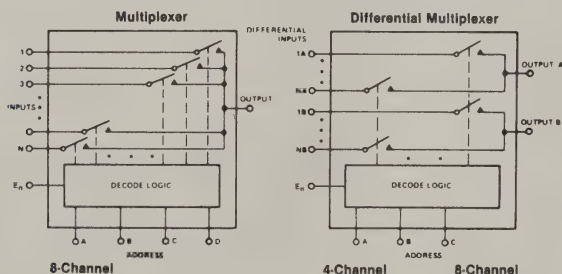
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## ANALOG MULTIPLEXERS

Basic Part No.	Process Type	Analog Voltage Range (V) (Note 4)	I <sub>DS(on)</sub> Max (Ω) (Note 4)	I <sub>D(off)</sub> (nA)	Transition Time (μsec) (Note 2)	Logic Levels (V)		Supply Voltage (V)		Comments
						V <sub>INL</sub>	V <sub>INH</sub>	(+) Sup. V+	(-) Sup. V-	
EIGHT CHANNEL MUX + ENABLE										
DG501	PMOS	+ 5 to - 5	150-240	8	1.5	0.6	3.5	5	- 20	Logic Pullup Resistors
DG503	PMOS	+ 10 to - 10	150-800	8	1.5	0.6	8.5	10	- 20	
DG508A	CMOS	+ 10 to - 15	400	10	1.0	0.8	2.4	15	- 15	Break-Before-Make
DG528	CMOS	+ 15 to - 15	400	10	1.0	0.8	2.4	+ 15	- 15	Latches On Inputs
SIXTEEN CHANNEL MUX + ENABLE										
DG506A	CMOS	+ 15 to - 15	400	10	1.0	0.8	2.4	15	- 15	Break-Before-Make
FOUR CHANNEL DIFFERENTIAL MUX + ENABLE										
DG509A	CMOS	+ 15 to - 15	400	10	1.0	0.8	2.4	15	- 15	Break-Before-Make
DG529	CMOS	+ 15 to - 15	400	10	1.0	0.8	2.4	15	- 15	Latches On Inputs
EIGHT CHANNEL DIFFERENTIAL MUX + ENABLE										
DG507A	CMOS	+ 15 to - 15	400	5	1.0	0.8	2.4	+ 15	- 15	Break-Before-Make

### Switch Configurations



#### NOTES:

1. The devices shown in **boldface** are recommended parts for new designs.
2. The appropriate switching characteristic for multiplexers is  $t_{TRANSITION}$ , not  $t_{ON}$ ,  $t_{OFF}$ .
3.  $V_{REF} = 1.5$  V is used when supply voltages  $< \pm 15$  V are used. Not needed when supply voltages of  $\pm 15$  are used.
4. Analog voltage range is a function of supply voltages. Where a FET switch is PMOS or CMOS,  $r_{DS}$  is also a function of Supply Voltage and Analog Voltage. See individual data sheets for more detail. Values shown are for temperature suffix A.
5. Device normally operates with resistor to + 10 V.

*Stresses listed under "Absolute Maximum Ratings" may be applied (one at a time) to devices without resulting in permanent damage. This is a stress rating only and not subject to production testing. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.*



# 8-Channel Multiplex Switch with Decode

## *designed for . . .*



DG501

- **Multiplexing Signals**
- **Data Acquisition**

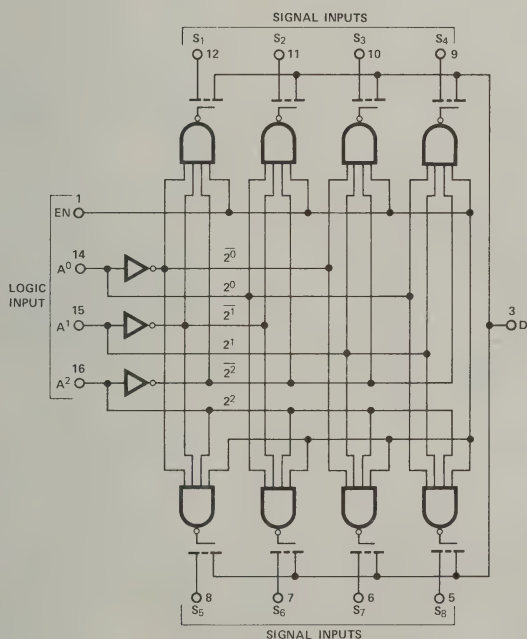
### BENEFITS

- **Reduces Cross-Talk in Systems**
  - Break-Before-Make Switching
- **Easily Interfaced**
  - Pull-Up Resistors on Inputs for TTL Compatibility

### DESCRIPTION

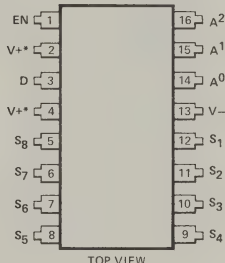
The DG501 is designed to function as a single-pole, 8-position (plus OFF) electronic switch. The function is implemented by using eight P-channel MOS field-effect transistors as analog switches. In the ON state, each switch will conduct current equally well in either direction and in the OFF state each switch will block voltages up to 10 V peak-to-peak. The ON-OFF state of each switch is controlled by drivers, which are in turn controlled by a 3-bit binary word plus an Enable-Inhibit input. The truth table shown below indicates the binary word required to select any one of the eight switch positions. Logic input levels "L" and "H" correspond to positive logic "0" and "1". Assuming supply voltages of +5 V and -20 V, logic "L"  $\leq 0.6$  V and logic "H"  $\geq 3.5$  V. "Pull-up" resistors are provided at each logic input to improve TTL compatibility. The rise and fall times of the drivers are designed to provide break-before-make switch action.

### FUNCTIONAL DIAGRAM



### PIN CONFIGURATION

#### Dual-In-Line Package



ORDER NUMBERS: DG501AP OR DG501BP  
SEE PACKAGE 12

DG501CJ  
SEE PACKAGE 8

\*Both V+ lines are internally connected, either one or both may be used. V+ common to substrate.

### TRUTH TABLE

LOGIC INPUTS				CHANNEL
A <sup>0</sup>	A <sup>1</sup>	A <sup>2</sup>	En	'ON'
L	L	L	H	S <sub>1</sub>
H	L	L	H	S <sub>2</sub>
L	H	L	H	S <sub>3</sub>
H	H	L	H	S <sub>4</sub>
L	L	H	H	S <sub>5</sub>
H	L	H	H	S <sub>6</sub>
L	H	H	H	S <sub>7</sub>
H	H	H	H	S <sub>8</sub>
X	X	X	L	OFF

4  
Analog Multiplexers

# ABSOLUTE MAXIMUM RATINGS

V+ to V-	-0.3, +30 V
V+ to V <sub>A</sub> , V <sub>EN</sub>	-0.3, +30 V
V+ to V <sub>D</sub> or V <sub>S</sub>	-0.3, +30 V
V <sub>D</sub> to V <sub>S</sub>	±25 V
V <sub>A</sub> , V <sub>EN</sub> to V-	30 V
V <sub>D</sub> or V <sub>S</sub> to V-	30 V
Current (Any Terminal)	-20 mA
Storage Temperature (A & B Suffix)	-65 to 150°C
(C Suffix)	-65 to 125°C

Operating Temperature (A Suffix)	-55 to 125°C
(B Suffix)	-20 to 85°C
(C Suffix)	0 to 70°C

## Power Dissipation\*

16 Pin DIP**	900 mW
16 Pin Plastic DIP***	470 mW

\*Device mounted with all leads welded or soldered to PC board.

\*\*Derate 12 mW/°C above 75°C

\*\*\*Derate 6.5 mW/°C above 25°C

# ELECTRICAL CHARACTERISTICS

All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC		MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V <sub>-</sub> = -20 V, V <sub>+</sub> = 5 V, V <sub>EN</sub> = 3.5 V V <sub>AL</sub> = 0.6 V, V <sub>AH</sub> = 3.5 V			
		DG501A			DG501B/C							
		-55°C	25°C	125°C	-20°C/ 0°C	25°C	85°C/ 70°C					
1	DS(on)	Drain-Source ON Resistance	150	150	225	150	150	200	Ω	V <sub>D</sub> = 5 V	I <sub>S</sub> = -1 mA, V <sub>-</sub> = -20 V	
2			200	200	300	200	200	300		V <sub>D</sub> = 0		
3			250	250	375	250	250	350		V <sub>D</sub> = -5 V		
4			200	200	300	200	200	300		V <sub>D</sub> = 5 V	I <sub>S</sub> = -100 μA, V <sub>-</sub> = -15 V	
5			250	250	375	250	250	350		V <sub>D</sub> = 0		
6			600	600	900	600	800	900		V <sub>D</sub> = -5 V		
7	IS(off)	Source OFF Leakage Current		-1	-1000		-3	-150	nA	V <sub>S</sub> = -5 V, V <sub>D</sub> = 5 V	V <sub>EN</sub> = 0.6 V	
8	ID(off)	Drain OFF Leakage Current			-8	-4000		-10		-500		V <sub>D</sub> = -5 V, V <sub>S</sub> = 5 V
9	ID(on) + IS(on)	Channel ON Leakage Current		8	4000		10	500		V <sub>D</sub> = V <sub>S</sub> = 5 V		
10	IINL	Input Current, Input Voltage Low		-1.2			-1.2		mA	V <sub>AL</sub> = 0		
11	IINH	Input Current, Input Current High		-150 Min			-150 Min			μA	V <sub>AH</sub> = 3.5 V	
12	ttransition	Switching Time of Multiplexer		1.5			2.0		μs	V <sub>-</sub> = -20 V	See Switching Time Test Circuit V <sub>S1</sub> = ±1 V, V <sub>S8</sub> = ±1 V, V <sub>S2-7</sub> = gnd	
13				2.5			3.0			V <sub>-</sub> = -15 V		
14	t <sub>on</sub>	Turn-ON Time		1.2 Typ*			1.2 Typ*				See Switching Time Test Circuit V <sub>S(all)</sub> = 1 V	
15	t <sub>off</sub>	Turn-OFF Time		0.8 Typ*			0.8 Typ*					
16	t <sub>open</sub>	Break-Before-Make Interval		0.05 Typ*			0.05 Typ*					
17	t <sub>on</sub>	Turn-ON Time		2.0 Typ*			2.0 Typ*		pF		Same as Above, Except V <sub>-</sub> = -15 V	
18	t <sub>off</sub>	Turn-OFF Time		0.8 Typ*			0.8 Typ*					
19	CS(off)	Source OFF Capacitance		10 Typ*			10 Typ*		pF	V <sub>S</sub> = V <sub>D</sub> = 5 V	V <sub>EN</sub> = 0.6 V, f = 1 MHz	
20	CD(off)	Drain OFF Capacitance		20 Typ*			20 Typ*					
21	I <sub>-</sub>	Drain Supply Current		-6			-6		mA	V <sub>EN</sub> = 0	All V <sub>A</sub> = 0	
22	I <sub>+</sub>	Source Supply Current		8			8					
23	I <sub>-</sub>	Drain Supply Current		-6			-6			V <sub>EN</sub> = 3.5 V		
24	I <sub>+</sub>	Source Supply Current		7			7					

\*Typical values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

IPAA

# APPLICATION HINTS\*

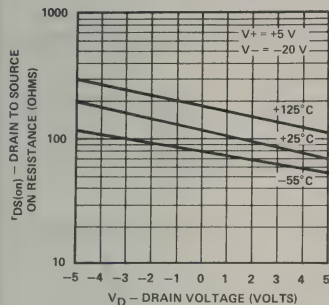
V+ Positive Supply Voltage (V)	V- Negative Supply Voltage (V)	V <sub>EN</sub> Enable Input Voltage Min High/ Max Low (V)	V <sub>IN</sub> Logic Input Voltage V <sub>INH</sub> Min/ V <sub>INL</sub> Max (V)	V <sub>S</sub> or V <sub>D</sub> Analog Signal Range (V)
+5**	-20	3.5/0.6	3.5/0.6	-5 to +5
+5	-15	3.5/0.6	3.5/0.6	-5 to +5

\*Application Hints are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

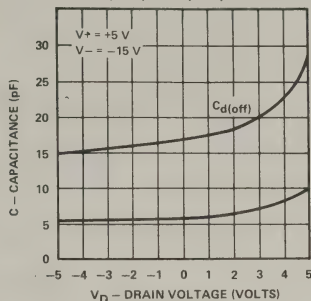
\*\*Electrical parameters chart based on V+ = 5 V, V- = -20 V.

# TYPICAL CHARACTERISTICS

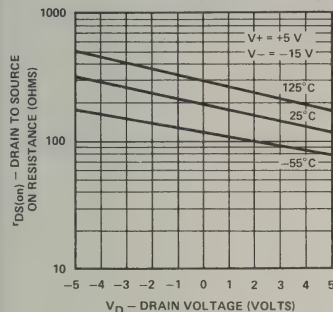
$r_{DS(on)}$  vs  $V_D$  and Temperature



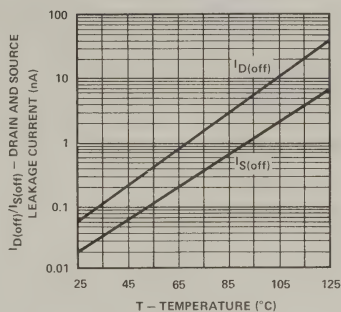
$C_D(off)$ ,  $C_S(off)$  vs  $V_D$



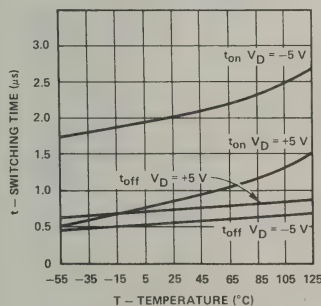
$r_{DS(on)}$  vs  $V_D$  and Temperature



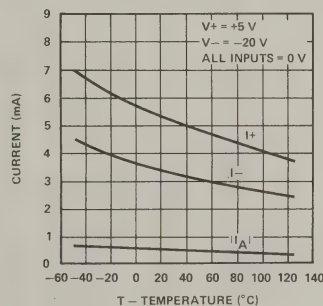
$I_{D(off)}/I_{S(off)}$  vs Temperature



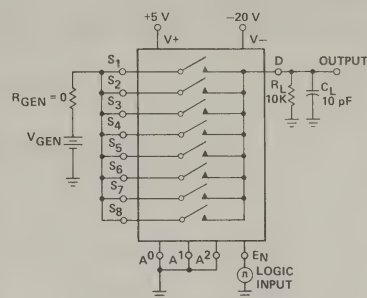
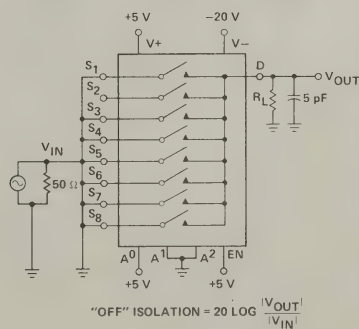
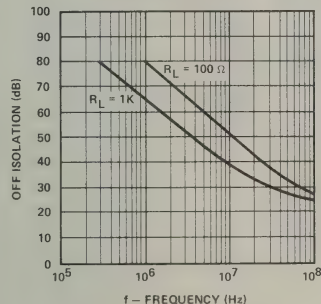
Switching Time vs Temperature



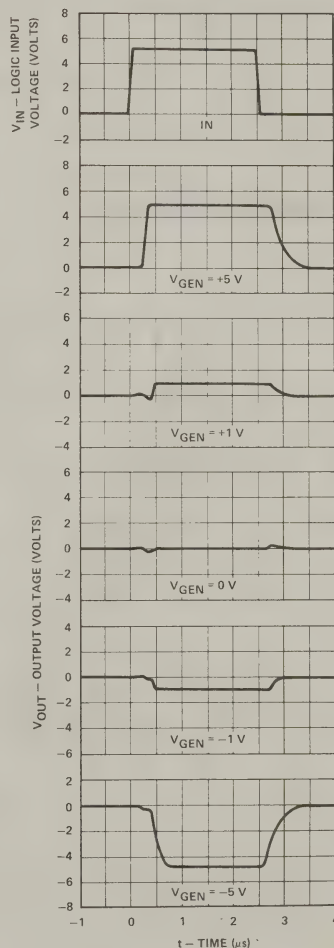
Supply Current vs Temperature



"OFF" Isolation vs  $R_L$  and Frequency

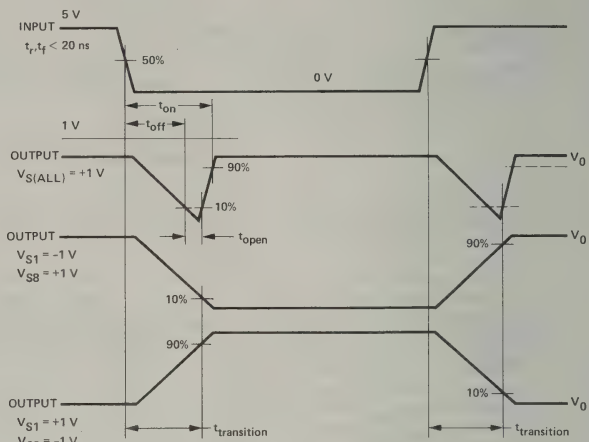
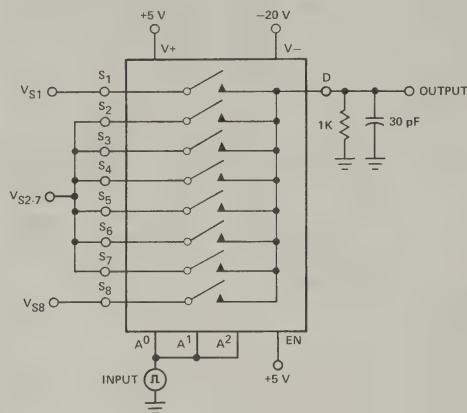


If  $R_{GEN}$ ,  $R_L$  or  $C_L$  is increased, there will be proportional increases in rise and/or fall RC times.

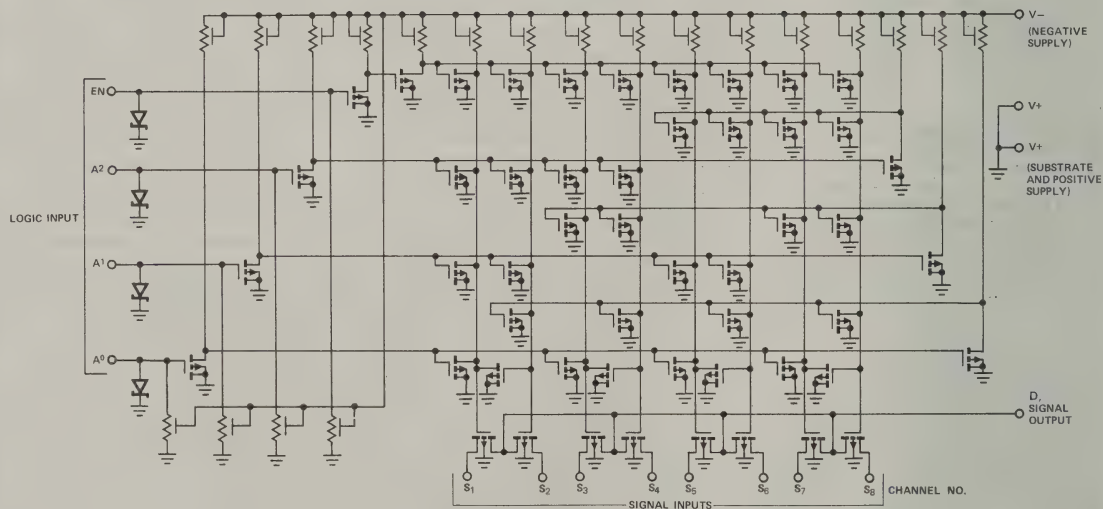


# SWITCHING TIME TEST CIRCUIT

Switch output waveform shown for  $V_S = \text{constant}$  with logic input waveform as shown. Note that  $V_S$  may be + or - as per switching time test circuit.  $V_O$  is the steady state output with switch on. Feedthrough via gate capacitance may result in spikes at leading and trailing edge of output waveform.



# SCHEMATIC DIAGRAM





# 8-Channel Multiplex Switch with Decode



DG503

*designed for . . .*

- Multiplexing Signals
- Data Acquisition

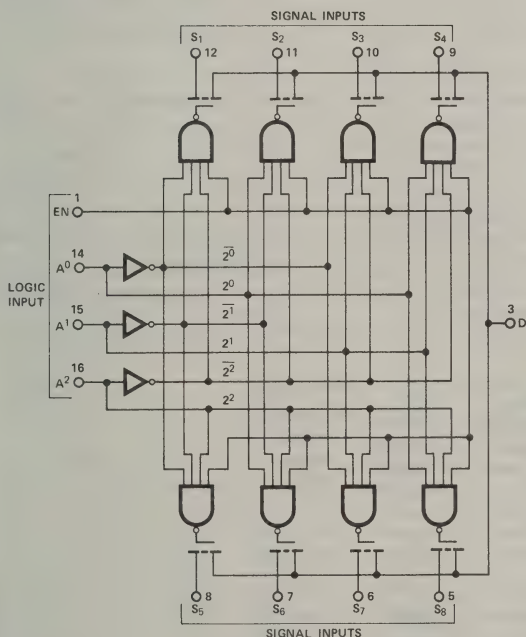
## BENEFITS

- Reduces Cross-Talk in Systems
  - Break-Before-Make Switching

## DESCRIPTION

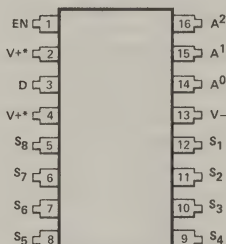
The DG503 is designed to function as a single-pole, 8-position (plus OFF) electronic switch. The function is implemented by using eight P-channel MOS field-effect transistors as analog switches. In the ON state, each switch will conduct current equally well in either direction, and in the OFF state each switch will block voltages up to 20 V peak-to-peak. The ON-OFF state of each switch is controlled by drivers, which are in turn controlled by a 3-bit binary word plus an Enable-Inhibit input. The truth table shown below indicates the binary word required to select any one of the eight switch positions. Logic input levels "L" and "H" correspond to positive logic "0" and "1". Assuming supply voltages of 10 and  $-20$  V, logic "L"  $\leq 0.6$  V and logic "H"  $\geq 8.5$  V. The rise and fall times of the drivers are designed to provide break-before-make switch action.

## FUNCTIONAL DIAGRAM



## PIN CONFIGURATION

Dual In-Line Package



TOP VIEW

ORDER NUMBERS: DG503AP OR DG503BP  
SEE PACKAGE 12

\* Both V+ lines are internally connected, either one or both may be used. V+ common to substrate.

## TRUTH TABLE

LOGIC INPUTS				CHANNEL
A <sup>0</sup>	A <sup>1</sup>	A <sup>2</sup>	En	'ON'
L	L	L	H	S <sub>1</sub>
H	L	L	H	S <sub>2</sub>
L	H	L	H	S <sub>3</sub>
H	H	L	H	S <sub>4</sub>
L	L	H	H	S <sub>5</sub>
H	L	H	H	S <sub>6</sub>
L	H	H	H	S <sub>7</sub>
H	H	H	H	S <sub>8</sub>
X	X	X	L	OFF

4  
Analog Multiplexers

# ABSOLUTE MAXIMUM RATINGS

V+ to V-	-0.3, 33 V
V+ to V <sub>A</sub> , V <sub>En</sub>	-0.3, 33 V
V+ to V <sub>D</sub> or V <sub>S</sub>	-0.3, 33 V
V <sub>D</sub> to V <sub>S</sub>	±25 V
V <sub>A</sub> , V <sub>En</sub> to V-	33 V
V <sub>D</sub> or V <sub>S</sub> to V-	33 V

Current (Any Terminal)	-20 mA
Storage Temperature (A & B Suffix)	-65 to 150°C
Operating Temperature (A Suffix)	-55 to 125°C
(B Suffix)	-20 to 85°C
Power Dissipation*	900 mW

\*All leads soldered or welded to PC board. Derate 12 mW/°C above 75°C

# ELECTRICAL CHARACTERISTICS

All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC				MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V <sub>-</sub> = -20 V, V <sub>+</sub> = 10 V, V <sub>En</sub> = 8.5 V V <sub>AL</sub> = 0.6 V, V <sub>AH</sub> = 8.5 V		
				A SUFFIX			B SUFFIX						
				-55°C	25°C	125°C	-20°C	25°C	85°C				
1	SWITCHING	r <sub>DS(on)</sub>	Drain-Source ON Resistance	150	150	225	150	150	200	Ω	V <sub>D</sub> = 10 V	I <sub>S</sub> = -1 mA	
2				250	250	375	250	250	350		V <sub>D</sub> = 0		
3				600	800	1250	600	800	1000		V <sub>D</sub> = -10 V		I <sub>S</sub> = -100 μA
4	H	I <sub>S(off)</sub>	Source OFF Leakage Current		-2	-2000		-3	-150	nA	V <sub>S</sub> = -10 V, V <sub>D</sub> = 10 V	V <sub>En</sub> = 0.6 V	
5		I <sub>D(off)</sub>	Drain OFF Leakage Current		-8	-4000		-10	-500		V <sub>D</sub> = -10 V, V <sub>S</sub> = 10 V		
6		I <sub>D(on)</sub> + I <sub>S(on)</sub>	Channel ON Leakage Current		8	4000		10	500		V <sub>D</sub> = V <sub>S</sub> = 10 V		
7	I <sub>N</sub>	I <sub>NL</sub>	Input Current, Input Voltage Low		-1			-1		μA	V <sub>AL</sub> = 0		
8	DYNAMIC	t <sub>transition</sub>	Switching Time of Multiplexer		1.5			2.0		μs	See Switching Time Test Circuit V <sub>S1</sub> = ±1 V, V <sub>S8</sub> = ±1 V, V <sub>S2-7</sub> = gnd		
9		t <sub>on</sub>	Turn-ON Time		1.2 Typ*			1.2 Typ*			See Switching Time Test Circuit V <sub>S(all)</sub> = ±1 V		
10		t <sub>off</sub>	Turn-OFF Time		0.8 Typ*			0.8 Typ*					
11		t <sub>open</sub>	Break-Before-Make Interval		0.05 Typ*			0.05 Typ*					
12	C	C <sub>S(off)</sub>	Source OFF Capacitance		5 Typ*			5 Typ*		pF	V <sub>S</sub> = V <sub>D</sub> = 0	V <sub>En</sub> = 0.5 V, f = 1 MHz	
13		C <sub>D(off)</sub>	Drain OFF Capacitance		20 Typ*			20 Typ*					
14	SUPPLY	I <sub>-</sub>	Drain Supply Current		-6			-6		mA	V <sub>En</sub> = 0		
15		I <sub>+</sub>	Source Supply Current		8			8			V <sub>En</sub> = 8.5 V, V <sub>A</sub> = 0		
16		I <sub>-</sub>	Drain Supply Current		-6			-6					
17		I <sub>+</sub>	Source Supply Current		7			7					

\*Typical values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

IPAA

# APPLICATION HINTS\*

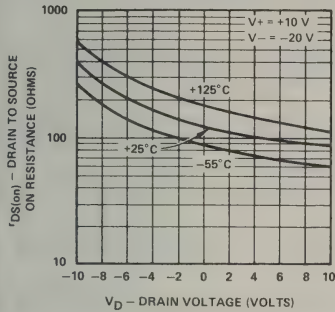
V+ Positive Supply Voltage (V)	V- Negative Supply Voltage (V)	V <sub>En</sub> Enable Input Voltage Min High/ Max Low (V)	V <sub>IN</sub> Logic Input Voltage VINH Min/ VINL Max (V)	V <sub>S</sub> or V <sub>D</sub> Analog Signal Range (V)
+10**	-20	8.5/0.6	8.5/0.6	-10 to +10
+5	-20	3.5/0.6	3.5/0.6	-10 to +5
+10	-15	8.5/0.6	8.5/0.6	-5 to +10
+5	-15	3.5/0.6	3.5/0.6	-5 to +5

\*Application Hints are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

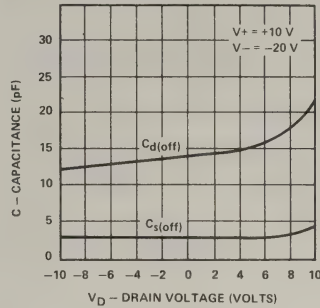
\*\*Electrical parameters chart based on V+ = +10 V, V- = -20 V.

# TYPICAL CHARACTERISTICS

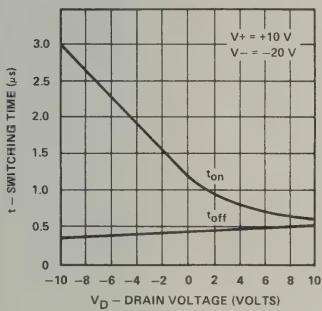
$r_{DS(on)}$  vs  $V_D$  and Temperature



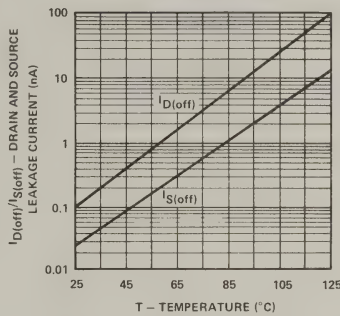
$C_{D(off)}$ ,  $C_{S(off)}$  vs  $V_D$



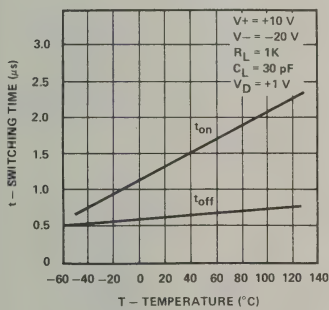
Switching Time vs  $V_D$



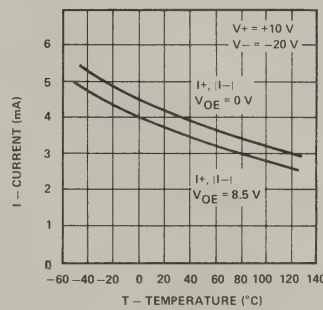
$I_{D(off)}$ ,  $I_{S(off)}$  vs Temperature



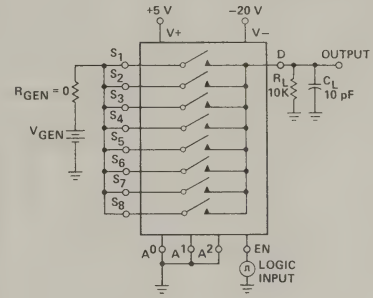
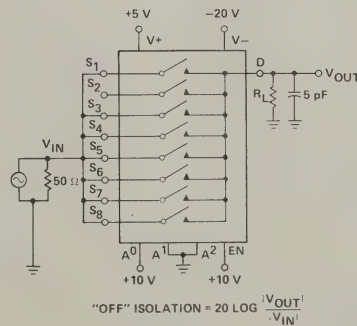
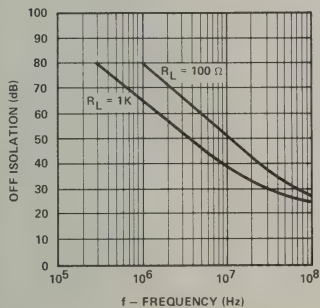
Switching Time vs Temperature



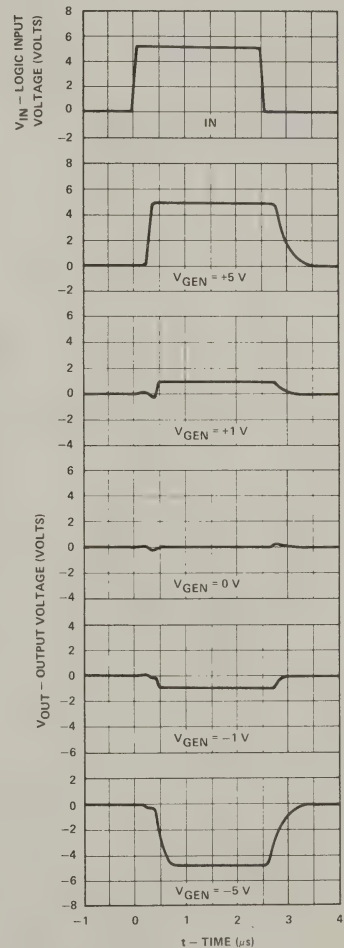
Supply Current vs Temperature



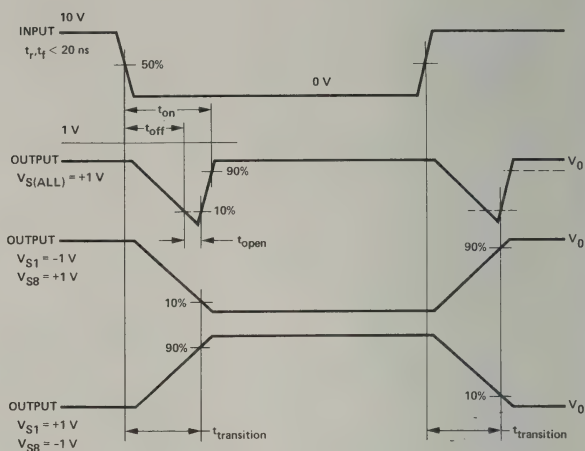
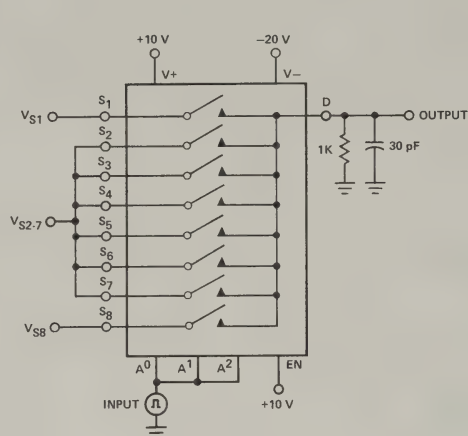
"OFF" Isolation vs  $R_L$  and Frequency



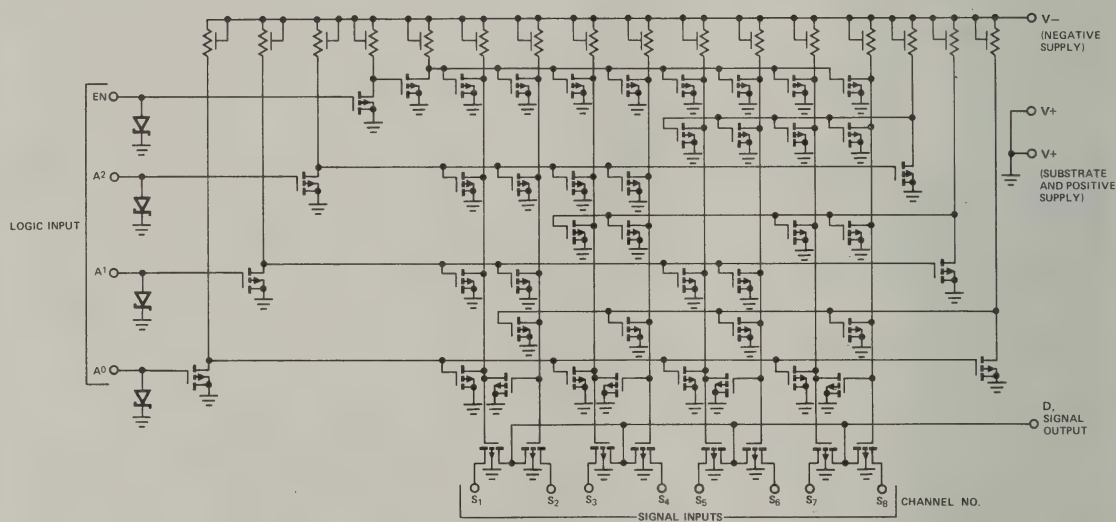
If  $R_{GEN}$ ,  $R_L$  or  $C_L$  is increased, there will be proportional increases in rise and/or fall RC times.



### SWITCHING TIME TEST CIRCUIT



### SCHEMATIC DIAGRAM





# Differential 8-Channel/ 16-Channel CMOS Analog Multiplexer designed for...



DG506 DG507

- Data Acquisition Systems
- Multiplexing Reference Signals
- Communication Systems

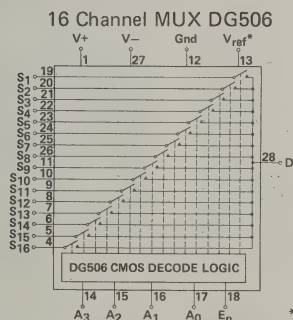
## DESCRIPTION

The DG506 is a single-pole 16-position (plus OFF) electronic switch array [DG507 is a double-pole 8-position (plus OFF)] which employs 16 pairs of complementary MOS (CMOS) field-effect transistors designed to function as analog switches. In the ON condition each switch will conduct current in either direction, and in the OFF condition each switch will block voltages up to 30 volts peak-to-peak. The ON-OFF state of each switch is controlled by drivers, which are in turn controlled by a 4-bit binary word (DG507 by a 3-bit binary word) input plus an Enable-Inhibit input. The truth table below shows the binary word required to select any one of the 16 switch positions, provided a positive logic "1" is present at the Enable Input. With logic "0" at the Enable input all switches will be OFF. The logic decoder and the Enable inputs will recognize voltages between 0 and 0.8 V as logic "0" voltages, and voltages between 2.4 and 15 V as logic "1" voltages. The input can thus be directly interfaced with TTL, DTL, RTL, CMOS and certain PMOS circuits. Switch action is break-before-make. For new designs, use the DG506A and DG507A.

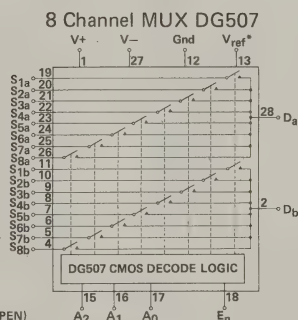
## BENEFITS

- Environmentally Rugged
  - Latchproof CMOS
- Easily Interfaced
  - TTL, DTL and CMOS Direct Control Over Military Temperature Range
- Low Stand-By Power
  - 36 mW Typical Stand-By Power
- Reduces System Cross-Talk
  - Break-Before-Make Switching Action
- Reduces External Component Requirements
  - $\pm 15$  V Analog Signal Range with  $\pm 15$  V Supplies

## FUNCTIONAL DIAGRAMS



\*OPTIONAL (NORMALLY LEFT OPEN)

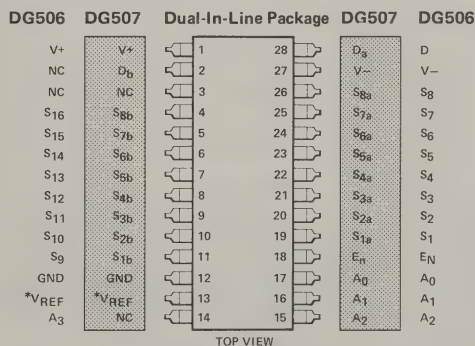


## TRUTH TABLE

A <sub>3</sub>	A <sub>2</sub>	A <sub>1</sub>	A <sub>0</sub>	E <sub>n</sub>	ON SWITCH	D G 5 0 6
X	X	X	X	0	NONE	
0	0	0	0	1	1	
0	0	0	1	1	2	
0	0	1	0	1	3	
0	0	1	1	1	4	
0	1	0	0	1	5	
0	1	0	1	1	6	
0	1	1	0	1	7	
0	1	1	1	1	8	
1	0	0	0	1	9	
1	0	0	1	1	10	
1	0	1	0	1	11	
1	0	1	1	1	12	
1	1	0	0	1	13	
1	1	0	1	1	14	
1	1	1	0	1	15	
1	1	1	1	1	16	

Logic "0" =  $V_{AL} \leq 0.8V$ , Logic "1" =  $V_{AH} \geq 2.4V$ , Screen is DG507

## PIN CONFIGURATIONS



\*OPTIONAL (NORMALLY LEFT OPEN)

V<sub>+</sub> COMMON TO SUBSTRATE

## ORDER NUMBERS:

DG506AR OR DG506BR DG506CJ

DG507AR OR DG507BR DG507C

SEE PACKAGE 13 SEE PACKAGE 14

Analog Multiplexers

# ABSOLUTE MAXIMUM RATINGS

$V_{IN}$ (A, En, or $V_{REF}$ ) to Ground	-0.3 V, $V_+$
$V_S$ or $V_D$ to $V_+$	0, -32 V
$V_S$ or $V_D$ to $V_-$	0, 32 V
$V_+$ to Ground	16 V
$V_-$ to Ground	-16 V
Current (Any Terminal, Except S or D)	30 mA
Continuous Current, S or D	20 mA
Peak Current, S or D	
(Pulsed at 1 msec, 10% Duty Cycle Max)	40 mA
Storage Temperature (A & B Suffix)	-65 to 150°C
(C Suffix)	-65 to 125°C

Operating Temperature (A Suffix)	-55 to 125°C
(B Suffix)	-20 to 85°C
(C Suffix)	0 to 70°C
Power Dissipation (Package)*	
28 Pin DIP**	1200 mW
28 Pin Plastic DIP***	625 mW

\* All leads soldered or welded to PC board.

\*\* Derate 16 mW/°C above 75°C.

\*\*\* Derate 8.3 mW/°C above 25°C.

# ELECTRICAL CHARACTERISTICS

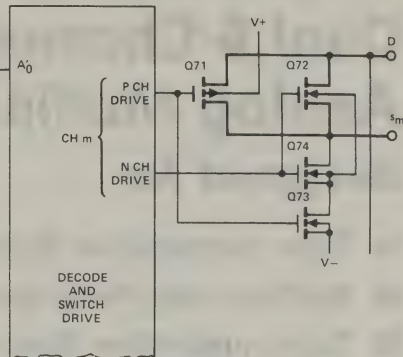
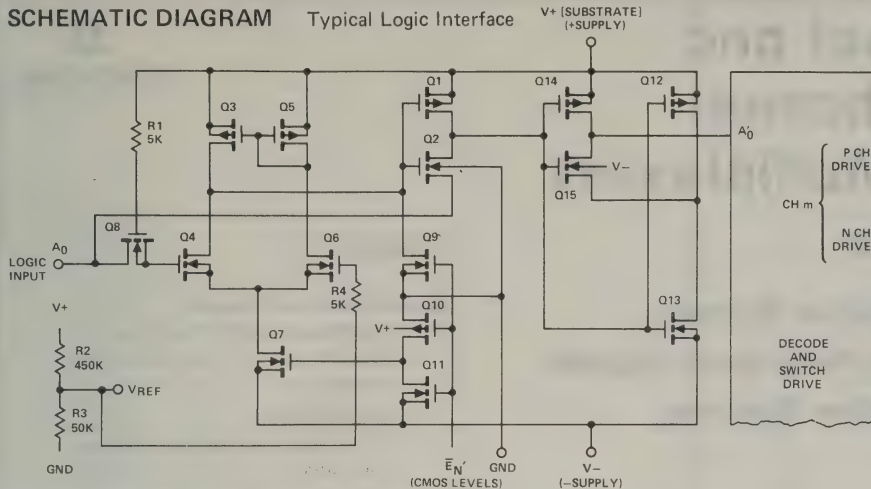
All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC			MEASURED TERMINAL	NO. TESTS PER TEMP	(Note 1) TYP 25°C	MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V+ = 15 V, V- = -15 V, Ground = 0, VREF = Open (Note 4)			
						A SUFFIX			B/C SUFFIX							
						-55°C	25°C	125°C	-20/0°C	25°C	85/70°C					
1	VANALOG	Minimum Analog Signal Handling Capability			±15		±15	±15		±15	±15	V	Switch ON IS = 10 mA			
2	rDS(on)	Drain Source ON Resistance	S to D	16	270	400	400	500	450	450	550	Ω	VD = 10 V, IS = -200 μA	Sequence each switch on		
3		ON Resistance		16	230	400	400	500	450	450	550		VD = -10 V, IS = -200 μA	VAL = 0.8 V, VAH = 2.4 V		
4	ΔrDS(on)	Greatest Change in Drain-Source ON Resistance Between Channels	S to D	16	6							%	$\Delta rDS(on) = \left( \frac{rDS(on)_{MAX} - rDS(on)_{MIN}}{rDS(on)_{AVE}} \right)$ -10 V < VS < 10 V			
5	SWITCH	IS(off)	Source OFF Leakage Current	S	16	-0.005		±1	±50		±5	±50	VS = 10 V, VD = -10 V	VEN = 0		
6					16	-0.005		±1	±50		±5	±50	VS = -10 V, VD = 10 V			
7		ID(off)	Drain OFF Leakage Current	DG506	D	1	-0.03		±10	±300		±20	±300		VD = 10 V, VS = -10 V	
8						1	-0.03		±10	±300		±20	±300		VD = -10 V, VS = 10 V	
9						2	-0.015		±5	±200		±10	±200		VD = 10 V, VS = -10 V	
10						2	-0.015		±5	±200		±10	±200		VD = -10 V, VS = 10 V	
11		ID(on) (Note 2)	Channel ON Leakage Current	DG506	D	16	-0.06		±10	±300		±20	±300		VS(all) = VD = 10 V	Sequence each switch on VAL = 0.8 V, VAH = 2.4 V
12						16	-0.06		±10	±300		±20	±300		VS(all) = VD = -10 V	
13						16	-0.03		±5	±200		±10	±200		VS(all) = VD = 10 V	
14						16	-0.03		±5	±200		±10	±200		VS(all) = VD = -10 V	
15	INPUT	IAH	Address Input Current, Input Voltage High		(5) 4	-0.002		-10	-30		-10	-30	VA = 2.4 V	μA		
16					(5) 4	0.006		10	30		10	30	VA = 15 V			
17		IA(peak)	Peak Address Input Current	A0, A1, A2, (A3) EN	(5) 4	-75							See Curve "IA vs VA"			
18		IAL	Address Input Current, Input Voltage Low		3	-0.002		-10	-30		-10	-30	VEN = 2.4 V		All VA = 0	
19				1	-0.002		-10	-30		-10	-30	VEN = 0				
20	DYNAMIC	ttransition	Switching Time of Multiplexer	D		0.6		1					See Figure 1	μs		
21		topen	Break-Before-Make Interval	D		0.2										
22		ton(EN)	Enable Turn-ON Time	D	1	1.0		1.5					See Figure 2			
23		toff(EN)	Enable Turn-OFF Time	D	1	0.4		1								
24	OFF ISOLATION	OFF Isolation (Note 3)		D		68							dB	VEN = 0, RL = 1K Ω, CL = 15 pF VS = 7 VRMS, f = 500 KHz		
25		CS(off)	Source OFF Capacitance	S	16	6							pF	VS = 0	VEN = 0, f = 140 KHz	
26		CD(off)	Drain OFF Capacitance	DG506	D	1	45							VD = 0		
27				DG507		2	23									
28	SUPPLY	I+	Positive Supply Current	V+	1	5.2		10				10	VEN = 5 V	All VA = 0		
29		I-	Negative Supply Current	V-	1	-5.2		-10				-10				
30		I+	Positive Supply Current	V+	1	1.2		2.5				2.5	VEN = 0			
31		I-	Negative Supply Current	V-	1	-1.2		-2.5				-2.5				

## NOTES:

- Typical Values are for DESIGN AID ONLY, not guaranteed and not subject to production testing
- $I_D(on)$  is leakage from driver into "ON" switch.
- OFF Isolation  $\Delta \approx 20 \log \frac{|V_D|}{|V_S|}$   $V_S$  = input to "OFF" switch  $V_D$  = output due to  $V_S$ .
- Functional operation is possible for supply voltages less than 15 V, but the input logic threshold will shift. For  $V_+ = |V_-| < 10$  V, 1.5 V may be applied to the  $V_{REF}$  terminal. The  $V_{REF}$  terminal has  $R_{IN} \approx 45$  K Ω (See the applications section.)

DG506 ICXBA  
DG507 ICXBB



## SWITCHING TIME TEST CIRCUIT

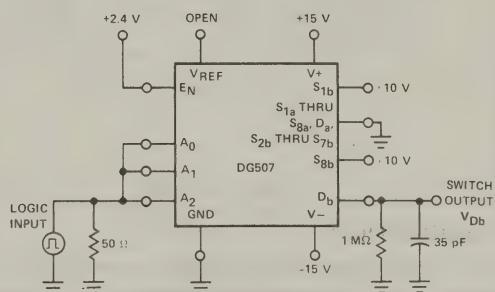
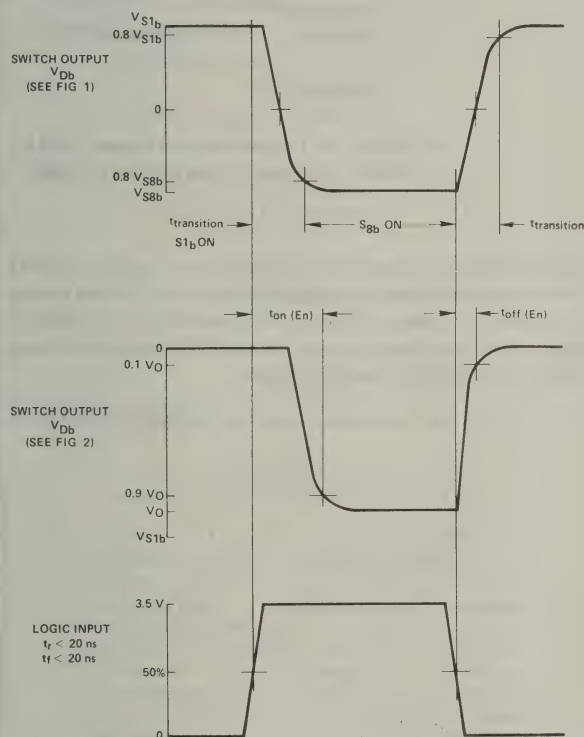


Figure 1

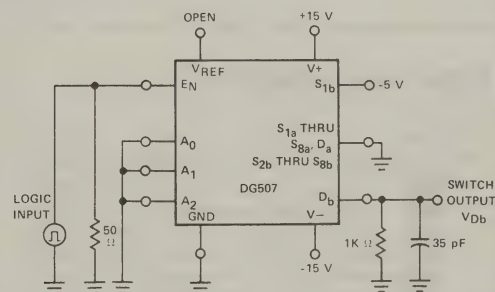


Figure 2

## APPLICATIONS

## Application Hints\*

V+ Positive Supply Voltage (V)	V- Negative Supply Voltage (V)	VREF Reference Pin Connection (V)	VIN Logic Input Voltage VINH Min/ VINL Max (V)	VS or VD Analog Voltage Range (V)
+15**	-15	Open	2.4/0.8	-15 to +15
+12	-12	Open or 1.4 V	2.4/0.8	-12 to +12
+10	-10	1.4 V	2.4/0.8	-10 to +10
+8***	-8	1.4 V	2.4/0.8	-8 to +8

\*Application Hints are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

\*\*Electrical Characteristics chart based on V+ = +15 V, V- = -15 V, VREF = Open.

\*\*\*Operation below  $\pm 8$  V is not recommended.



# 16-Channel and Dual 8-Channel Analog Multiplexers designed for . . .

- Data Acquisition Systems
- Multiplexing Reference Signals
- Communication Systems

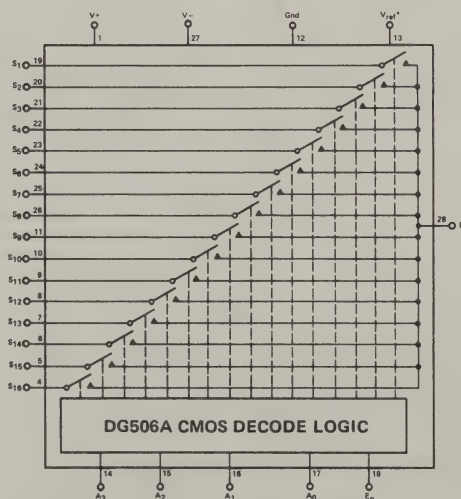
## BENEFITS

- Environmentally Rugged
  - 40V Power Supply Max Rating
  - Static Protected Logic Inputs
  - Latchproof
- Easily Interfaced
  - TTL Compatible without Pull-Up Resistors
- Improved System Accuracy
  - $r_{DS(on)} < 400\Omega$
  - $V_{ERROR} = 150 \text{ Microvolts at } 125^\circ\text{C}$   
 $= I_{D(on)} \times r_{DS(on)}$
  - $\Delta r_{DS(on)} < 6\%$   
for  $-10V < V_{ANA} < +10V$
- Pin for Pin Compatible with Intersil IH6116, Harris HI506 and Analog Devices AD7506

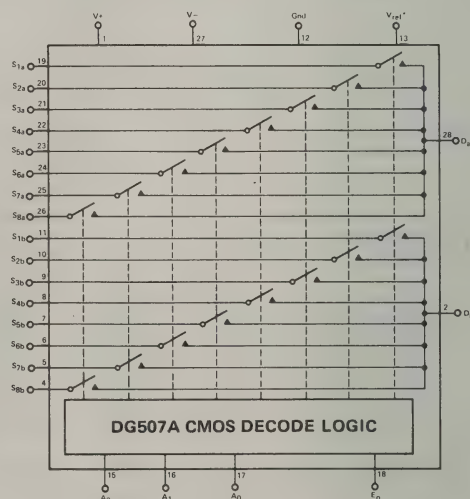
## DESCRIPTION

The DG506A and DG507A designed on the Siliconix PLUS-40 CMOS process provides solid state switch action with 400 ohms contact (ON) resistance and very high OFF resistance. True bidirectional switch action takes place over the full analog signal range of  $\pm 15$  volts, with Break-Before-Make operation to prevent momentary shorting of signal inputs. The DG506A provides 16 channel single ended multiplexing and demultiplexing of  $\pm 15$  volt analog signals. The DG507A provides 8 channel differential multiplexing and demultiplexing of  $\pm 15$  volt common mode plus differential signals.

## FUNCTIONAL DIAGRAMS



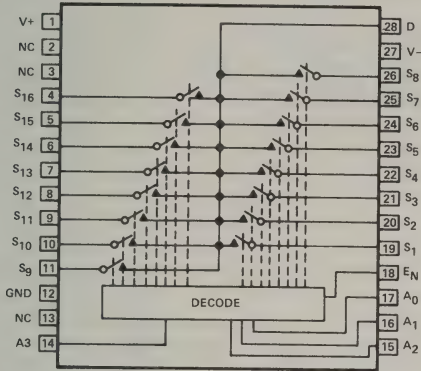
**DG506A**  
16 CHANNEL SINGLE ENDED MULTIPLEXER



**DG507A**  
DIFFERENTIAL 8 CHANNEL MULTIPLEXER



Dual-In-Line Package

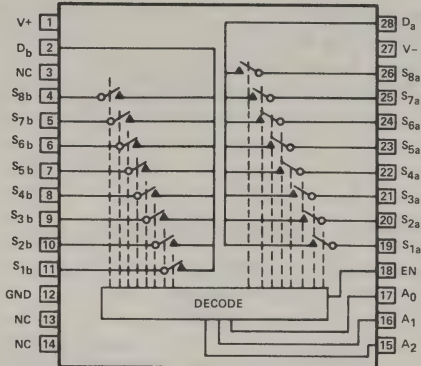


Top View

ORDER NUMBERS:  
DG506AAR OR DG506ABR  
SEE PACKAGE 13

DG506ACJ  
SEE PACKAGE 14

Dual-In-Line Package



Top View

ORDER NUMBERS:  
DG507AAR OR DG507ABR  
SEE PACKAGE 13

DG507ACJ  
SEE PACKAGE 14

TRUTH TABLES

DG506A

A <sub>3</sub>	A <sub>2</sub>	A <sub>1</sub>	A <sub>0</sub>	E <sub>n</sub>	ON SWITCH
X	X	X	X	0	NONE
0	0	0	0	1	1
0	0	0	1	1	2
0	0	1	0	1	3
0	0	1	1	1	4
0	1	0	0	1	5
0	1	0	1	1	6
0	1	1	0	1	7
0	1	1	1	1	8
1	0	0	0	1	9
1	0	0	1	1	10
1	0	1	0	1	11
1	0	1	1	1	12
1	1	0	0	1	13
1	1	0	1	1	14
1	1	1	0	1	15
1	1	1	1	1	16

DG507A

A <sub>2</sub>	A <sub>1</sub>	A <sub>0</sub>	E <sub>n</sub>	ON SWITCH
X	X	X	0	NONE
0	0	0	1	1
0	0	1	1	2
0	1	0	1	3
0	1	1	1	4
1	0	0	1	5
1	0	1	1	6
1	1	0	1	7
1	1	1	1	8

Logic "0" = V<sub>AL</sub> ≤ 0.8V, Logic "1" = V<sub>AH</sub> ≥ 2.4V

# **ABSOLUTE MAXIMUM RATINGS**

Voltages referenced to V-

V+ ..... 44 V

GND. .... 25 V

Digital inputs<sup>5</sup> V<sub>S</sub>, V<sub>D</sub>. .... -2 V to (V<sup>+</sup> + 2 V) or  
20 mA, whichever occurs first.

Current (Any Terminal, Except S or D) ..... 30 mA

Continuous Current, S or D ..... 20 mA

Peak Current, S or D

(Pulsed at 1 msec, 10% Duty Cycle Max) .... 40 mA

Storage Temperature (A & B Suffix) ..... -65 to 150°C

(C Suffix) ..... -65 to 125°C

Operating Temperature (A Suffix) ..... -55 to 125°C

(B Suffix) ..... -20 to 85°C

(C Suffix) ..... 0 to 70°C

Power Dissipation (Package)\*

28 Pin DIP\*\* ..... 1200 mW

28 Pin Plastic DIP\*\*\* ..... 625 mW

\* All leads soldered or welded to PC board.

\*\* Derate 16 mW/°C above 75°C.

\*\*\* Derate 8.3 mW/°C above 25°C.

## **ELECTRICAL CHARACTERISTICS**

All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC			MEASURED TERMINAL	NO. TESTS PER TEMP.	(Note 1) TYP 25°C	MAX LIMITS					UNIT	TEST CONDITIONS, UNLESS NOTED: V <sup>+</sup> = 15 V, V <sup>-</sup> = -15 V, Ground = 0, (Note 4)				
						A SUFFIX			B/C SUFFIX							
						-55°C	25°C	125°C	-20/0°C	25°C	85/70°C					
1	V <sub>ANALOG</sub>	Minimum Analog Signal Handling Capability			±15		±15	±15		±15	±15	V				
2	r <sub>DS(on)</sub>	Drain Source ON Resistance	S to D	16	270	400	400	500	450	450	550	Ω	V <sub>D</sub> = 10 V, I <sub>S</sub> = -200 μA	Sequence each switch on V <sub>AL</sub> = 0.8 V, V <sub>AH</sub> = 2.4 V V <sub>D</sub> = -10 V, I <sub>S</sub> = -200 μA V <sub>EN</sub> = 2.4 V		
3				16	230	400	400	500	450	450	550					
4	Δr <sub>DS(on)</sub>	Greatest Change in Drain-Source ON Resistance Between Channels	S to D	16	6							%	$\Delta r_{DS(on)} = \frac{(r_{DS(on)}^{MAX} - r_{DS(on)}^{MIN})}{r_{DS(on)}^{AVE}}$ -10 V < V <sub>S</sub> < 10 V			
5	SWITCH	I <sub>S(off)</sub>	S	16	0.002		±1	±50		±5	±50	nA	V <sub>S</sub> = 10 V, V <sub>D</sub> = -10 V	V <sub>EN</sub> = 0		
6					16	-0.005		±1	±50		±5		±50		V <sub>S</sub> = -10 V, V <sub>D</sub> = 10 V	
7		I <sub>D(off)</sub>	D	1	0.020		±10	±300		±20	±300		V <sub>D</sub> = 10 V, V <sub>S</sub> = -10 V			
8					1	-0.03		±10	±300		±20		±300		V <sub>D</sub> = -10 V, V <sub>S</sub> = 10 V	
9					2	0.007		±5	±200		±10		±200		V <sub>D</sub> = 10 V, V <sub>S</sub> = -10 V	
10					2	-0.015		±5	±200		±10		±200		V <sub>D</sub> = -10 V, V <sub>S</sub> = 10 V	
11		I <sub>D(on)</sub> <sup>2</sup>	Channel ON Leakage Current	D	16	0.03		±10	±300		±20		±300		V <sub>S(all)</sub> = V <sub>D</sub> = 10 V	Sequence each switch on V <sub>AL</sub> = 0.8 V, V <sub>AH</sub> = 2.4 V V <sub>EN</sub> = 2.4 V
12						16	-0.06		±10	±300			±20		±300	
13					16	0.015		±5	±200		±10	±200	V <sub>S(all)</sub> = V <sub>D</sub> = 10 V			
14					16	-0.03		±5	±200		±10	±200	V <sub>S(all)</sub> = V <sub>D</sub> = -10 V			
15	INPUT	I <sub>AH</sub>	Address Input Current, Input Voltage High	A <sub>0</sub> , A <sub>1</sub> , A <sub>2</sub> , (A <sub>3</sub> ) EN	(5) 4	-0.002		-10	-30		-10	-30	V <sub>A</sub> = 2.4 V	All V <sub>A</sub> = 0		
16						(5) 4	0.006		10	30		10	30		V <sub>A</sub> = 15 V	
17		I <sub>AL</sub>	Address Input Current, Input Voltage Low	3	-0.002		-10	-30		-10	-30	V <sub>EN</sub> = 2.4 V				
18					1	-0.002		-10	-30		-10	-30	V <sub>EN</sub> = 0			
19	DYNAMIC	t <sub>transition</sub>	Switching Time of Multiplexer	D	1	0.6		1				μs	See Figure 1			
20		t <sub>open</sub>	Break-Before-Make Interval	D		0.2							See Figure 3			
21		t <sub>on(EN)</sub>	Enable Turn-ON Time	D	1	1.0		1.5					See Figure 2			
22		t <sub>off(EN)</sub>	Enable Turn-OFF Time	D	1	0.4		1								
23	OIRR	OFF Isolation (Note 3)	D		68							dB	V <sub>EN</sub> = 0, R <sub>L</sub> = 1K Ω, C <sub>L</sub> = 15 pF, V <sub>S</sub> = 7 VRMS, f = 500 KHz	V <sub>EN</sub> = 0, f = 140 KHz		
24	C <sub>S(off)</sub>	Source OFF Capacitance	S	16	6							pF	V <sub>S</sub> = 0			
25	C <sub>D(off)</sub>	Drain OFF Capacitance	D	1	45								V <sub>D</sub> = 0			
26					DG507A	2	23									
27	SUPPLY	I <sup>+</sup>	Positive Supply Current	V <sup>+</sup>		1.3		2.4		2.4		mA	V <sub>EN</sub> = 0 V or 5 V	All V <sub>A</sub> = 0		
28		I <sup>-</sup>	Negative Supply Current	V <sup>-</sup>		-0.7		-1.5		-1.5						

**DG506A ICMH-A**  
**DG507A ICMH-B**

### **NOTES:**

1. Typical values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

2. I<sub>D(on)</sub> is leakage from driver into "ON" switch.

3. OFF position = 20 log  $\frac{V_D}{V_S}$ , V<sub>S</sub> = input to "OFF" switch, V<sub>D</sub> = output due to V<sub>S</sub>.

4. Functional operation is possible for supply voltages less than 15 V, but the input logic threshold will shift.

5. Signals on S<sub>X</sub>, D<sub>X</sub> or I<sub>NX</sub> exceeding V<sup>+</sup> or V<sup>-</sup> will be clamped by internal diodes. Limit forward diode current to maximum current ratings.

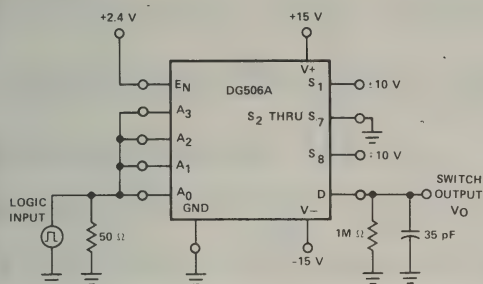


Figure 1(a)

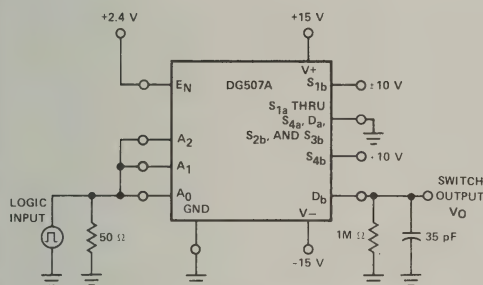


Figure 1(b)

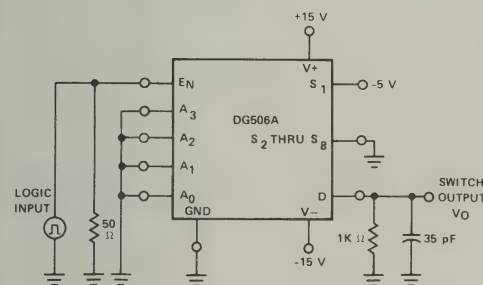


Figure 2(a)

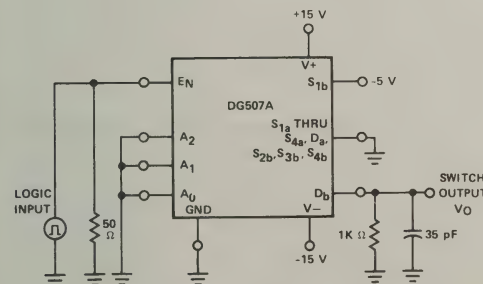


Figure 2(b)

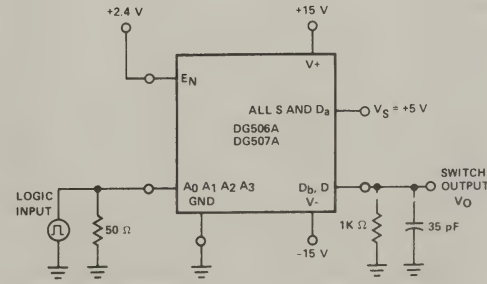
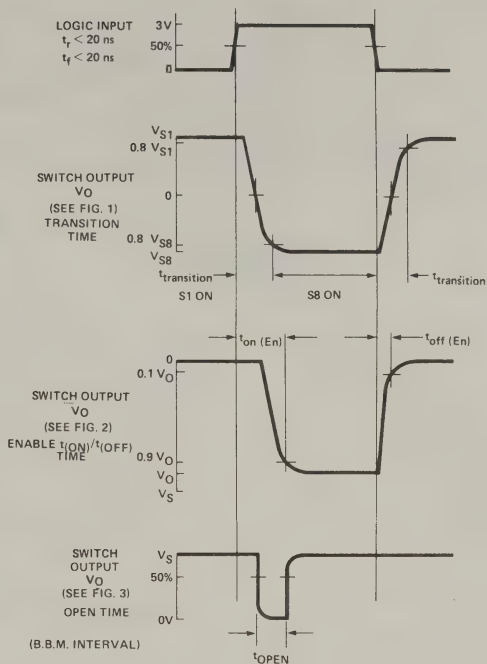
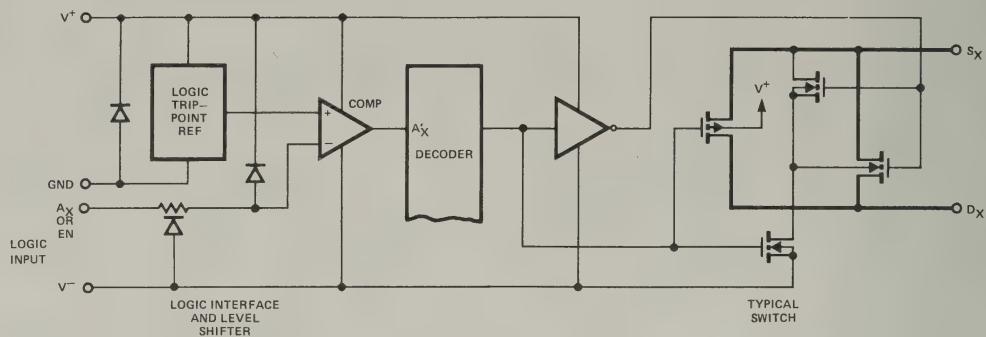


Figure 3

# SCHEMATIC DIAGRAM





# 8-Channel / 4-Channel Differential CMOS Analog Multiplexer designed for...

- Data Acquisition Systems
- Multiplexing Reference Signals
- Communication Systems

## DESCRIPTION

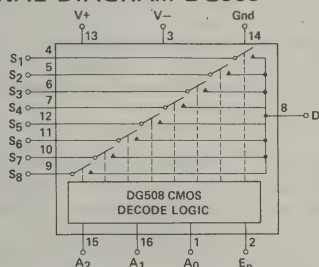
The DG508 is a single-pole 8-position (plus OFF) electronic switch array [DG509 double-pole, 4-position (plus OFF)], which employs 8 pairs of complementary MOS (CMOS) field-effect transistors designed to function as analog switches. In the ON condition each switch will conduct current in either direction, and in the OFF position each switch will block voltages up to 30 V peak-to-peak. The ON-OFF state of each switch is controlled by drivers, which are in turn controlled by a 3-bit binary word input plus an Enable/Inhibit input. The truth table below shows the binary word required to select any one of the 8 switch positions, provided a positive logic "1" is present at the Enable Input. With logic "0" at the Enable input all switches will be OFF. The logic decoder and the Enable inputs will recognize as logic "0" any voltage between 0 and 0.8 V, and any voltage between 2.4 and 15 V as logic "1" inputs. The inputs can thus be directly interfaced with TTL, DTL, RTL, CMOS and certain PMOS circuits. Delays are designed into logic decode and driver circuits to insure that switch action is break-before-make. For new designs, use DG508A and DG509A.

## DECODE TRUTH TABLE

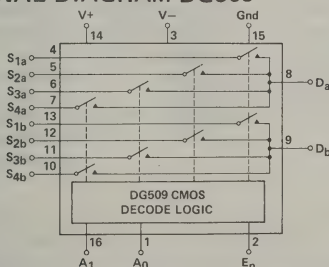
DG508	A <sub>2</sub>	A <sub>1</sub>	A <sub>0</sub>	En	ON SWITCH	DG509
	X	X	X	0	NONE	
	0	0	0	1	1	
	0	0	1	1	2	
	0	1	0	1	3	
	0	1	1	1	4	
	1	0	0	1	5	
	1	0	1	1	6	
	1	1	0	1	7	
	1	1	1	1	8	

Logic "1" =  $V_{AH} \geq 2.4 \text{ V}$   
 Logic "0" =  $V_{AL} \leq 0.8 \text{ V}$

## FUNCTIONAL DIAGRAM DG508



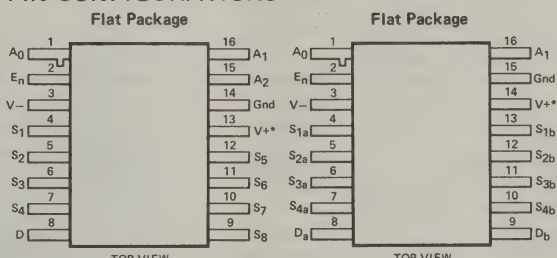
## FUNCTIONAL DIAGRAM DG509



## BENEFITS

- Easily Interfaced
  - TTL, DTL and CMOS Direct Control Over Military Temperature Range
- Low Stand-By Power
  - 36 mW Typical Stand-By Power
- Reduces System Cross-Talk
  - Break-Before-Make Switching Action
- Reduces External Component Requirements
  - $\pm 15 \text{ V}$  Analog Signal Range with  $\pm 15 \text{ V}$  Supplies
- Environmentally Rugged
  - Latch-proof CMOS

## PIN CONFIGURATIONS



### ORDER NUMBER:

DG508AL

SEE PACKAGE 17

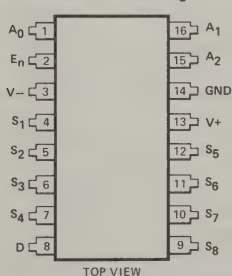
\*Common to Substrate and Base of Package

### ORDER NUMBER:

DG509AL

SEE PACKAGE 17

### Dual-In-Line Package



### ORDER NUMBERS:

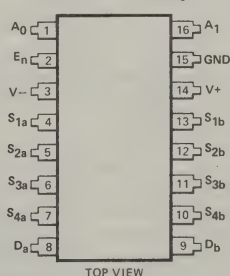
DG508AP OR DG508BP

SEE PACKAGE 12

DG508CJ

SEE PACKAGE 8

### Dual-In-Line Package



### ORDER NUMBERS:

DG509AP OR DG509BP

SEE PACKAGE 12

DG509CJ

SEE PACKAGE 8

## ABSOLUTE MAXIMUM RATINGS

$V_{IN}$ (A, EN) to Ground	-0.3 V, $V_+$
$V_S$ or $V_D$ to $V_+$	0, -32 V
$V_S$ or $V_D$ to $V_-$	0, 32 V
$V_+$ to Ground	16 V
$V_-$ to Ground	-16 V
Current (Any Terminal, Except S or D)	30 mA
Continuous Current, S or D	20 mA
Peak Current, S or D	
(Pulsed at 1 msec, 10% Duty Cycle Max)	40 mA
Operating Temperature (A Suffix)	-55 to 125°C
(B Suffix)	-20 to 85°C
(C Suffix)	0 to 70°C

Storage Temperature (A & B Suffix)	-65 to 150°C
(C Suffix)	-65 to 125°C
Power Dissipation (Package)*	
16 Pin DIP**	900 mW
16 Pin Plastic DIP***	470 mW
Flat Package****	750 mW

\* All leads soldered or welded to PC board.

\*\* Derate 12 mW/°C above 75°C

\*\*\* Derate 6.3 mW/°C above 25°C

\*\*\*\* Derate 10 mW/°C above 75°C

## ELECTRICAL CHARACTERISTICS

All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC				MEASURED TERMINAL	NO. TESTS PER TEMP.	TYP† 25°C	MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V+ = 15 V, V- = 15 V, Ground = 0	
							A SUFFIX			B/C SUFFIXES					
						-55°C	25°C	125°C	-20°C 0°C	25°C	85°C 70°C				
1	VANALOG	Minimum Analog Signal Handling Capability				±15		±15	±15		±15	±15	V	Switch ON IS = 10 mA	
2	SWITCH	rDS(on)	Drain-Source ON Resistance	S to D	8	270	400	400	500	450	450	550	Ω	VD = 10 V, IS = -200 μA	Sequence each switch on
3					8	230	400	400	500	450	450	500		VD = -10 V, IS = -200 μA	VAL = 0.8 V, VAH = 2.4 V
4		ΔrDS(on)	Greatest Change in Drain Source ON Resistance Between Channels	S to D	8	6								%	ΔrDS(on) = (rDS(on) MAX - rDS(on) MIN) / rDS(on) AVE
															-10 V ≤ VS ≤ 10 V
5	HIGH	IS(off)	Source OFF Leakage Current	S	8	-0.005		±1	±50		±5	±50	nA	VS = 10 V, VD = -10 V	VEN = 0
6					8	-0.005		±1	±50		±5	±50		VS = -10 V, VD = 10 V	
7		ID(off)	Drain OFF Leakage Current	D	1	-0.015		±10	±200		±20	±200		VD = 10 V, VS = -10 V	
8					1	-0.015		±10	±200		±20	±200		VD = -10 V, VS = 10 V	
9					2	-0.008		±10	±100		±20	±100		VD = 10 V, VS = -10 V	
10					2	-0.008		±10	±100		±20	±100		VD = -10 V, VS = 10 V	
11		ID(on)*	Drain ON Leakage Current	D	8	-0.03		±10	±200		±20	±200		VS(alt) = VD = 10 V	Sequence each switch on VAL = 0.8 V, VAH = 2.4 V
12					8	-0.03		±10	±200		±20	±200		VS(alt) = VD = -10 V	
13			8		-0.015		±10	±100		±20	±100	VS(alt) = VD = 10 V			
14			8		-0.015		±10	±100		±20	±100	VS(alt) = VD = -10V			
15	INPUT	IAH	Address Input Current, Input Voltage High	A0, A1 (A2)	(4) 3	-0.002		-10	-30		-10	-30	μA	VA = 2.4 V	All VA = 0
16					(4) 3	0.006		10	30		10	30		VA = 15 V	
17		IA(peak)	Peak Address Input Current	EN	(4) 3	-75								See Curve "IA vs VA"	
18		IAL	Address Input Current, Input Voltage Low	A0, A1 (A2)	(3) 2	-0.002		-10	-30		-10	-30		VEN = 2.4 V	
19				EN	1	-0.002		-10	-30		-10	-30	VEN = 0		
20	DYNAMIC	ttransition	Switching Time of Multiplexer	D		0.6		1					μs	See Figure 1	
21		topen	Break-Before-Make Interval	D		0.2									
22		ton(EN)	Enable Turn-ON Time	D	1	1.0		1.5							
23		ttoff(EN)	Enable Turn-OFF Time	D	1	0.4		1							
24		OFF Isolation**		D	8	68									
25	ANALOG	CS(off)	Source OFF Capacitance	S	8	5							pF	VEN = 0, RL = 1K Ω, CL = 15 pF VS = 7 VRMS, f = 500 kHz	VEN = 0, f = 140 kHz
26		CD(off)	Drain OFF Capacitance	DG508	D	1	25							VS = 0	
27				DG509	D	2	12							VD = 0	
28	SUPPLY	I+	Positive Supply Current	V+	1	3.5		8.0		8.0			mA	VEN = 5 V	All VA = 0
29		I-	Negative Supply Current	V-	1	-3.5		-8.0		-8.0					
30		I+ Standby	Positive Supply Current	V+	1	1.0		2.4		2.8					
31		I- Standby	Negative Supply Current	V-	1	-1.0		-2.4		-2.8					

ICX-A DG508

ICX-B DG509

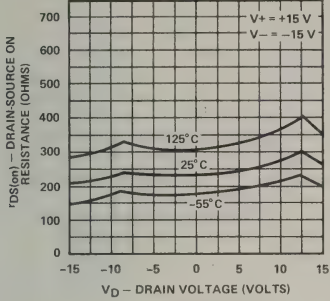
† Typical Values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

\*  $I_{D(on)}$  is leakage from driver into "ON" switch

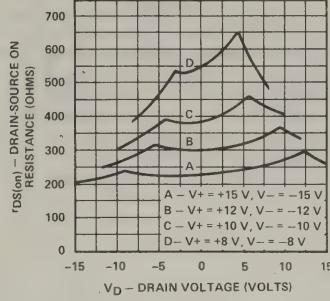
\*\* OFF isolation  $\hat{=}$   $20 \log \frac{|V_D|}{|V_S|}$ ,  $V_S$  = input to "OFF" switch,  $V_D$  = output due to  $V_S$ .

# TYPICAL CHARACTERISTICS

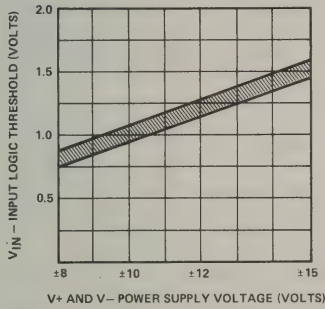
$r_{DS(on)}$  vs  $V_D$  and Temperature



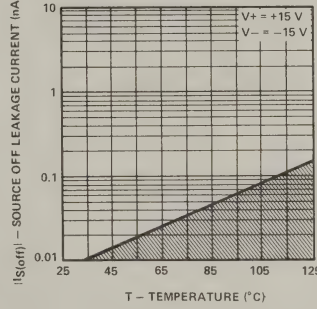
$r_{DS(on)}$  vs  $V_D$  and Power Supply Voltage



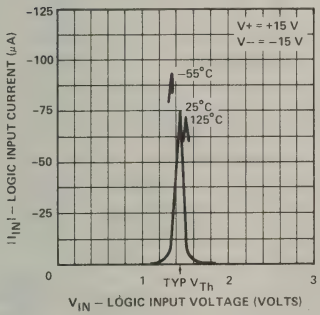
Logic Threshold vs Power Supply Voltage



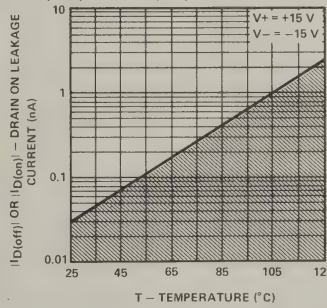
$I_{S(off)}$  vs Temperature\*



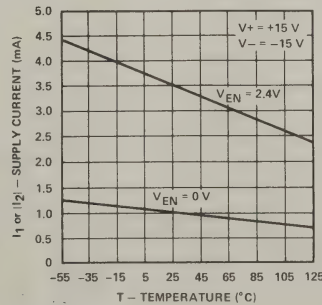
$I_A$  vs  $V_A$   
(Terminals A<sub>0</sub>, A<sub>1</sub>, A<sub>2</sub>, EN)



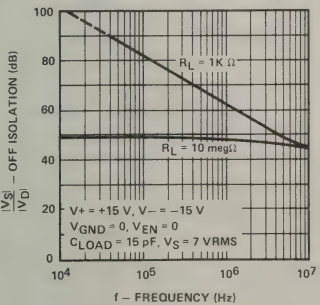
$I_{D(off)}$  and  $I_{D(on)}$  vs Temperature\*



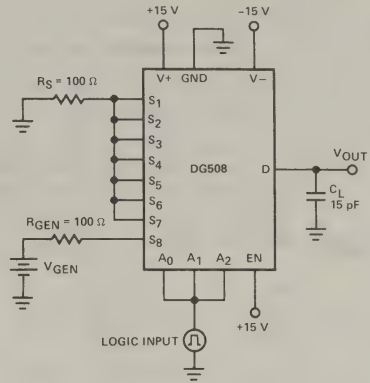
Power Supply Current vs Temperature



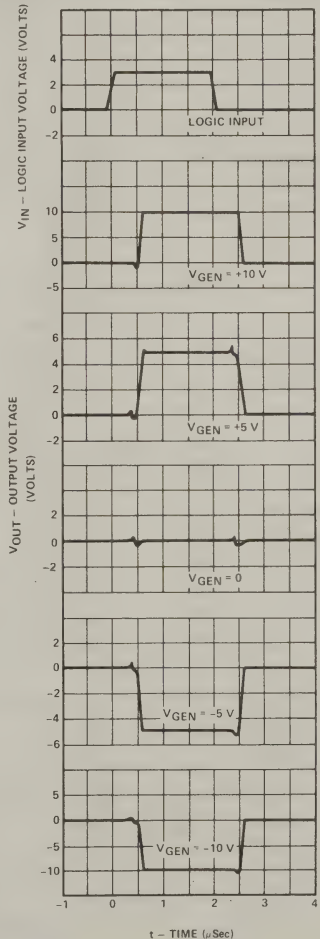
OFF Isolation vs Frequency



Typical delay, rise, fall, settling times, and switching transients in this circuit (similar circuit for DG509).



If  $R_{GEN}$ ,  $R_S$ , or  $C_L$  is increased, there will be proportional increases in rise and/or fall RC times.

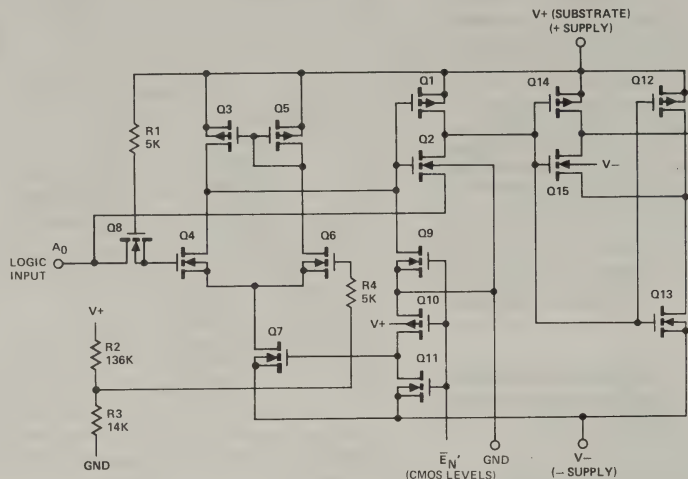


\*The net leakage into the source or drain is the n-channel leakage minus the p-channel leakage. This difference can be positive, negative, or zero depending on the analog voltage and temperature, and will vary greatly from unit to unit.

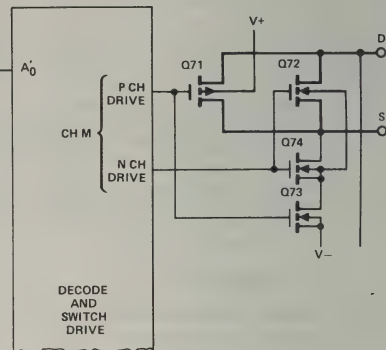


# SCHEMATIC DIAGRAM

## Typical Logic Interface



## Typical Switch



## SWITCHING TIME TEST CIRCUIT

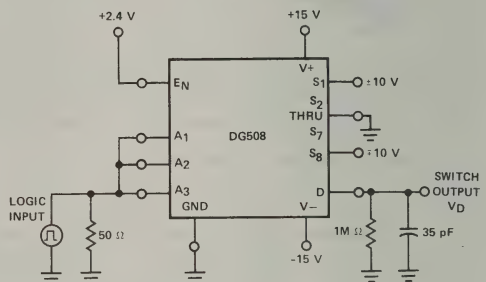
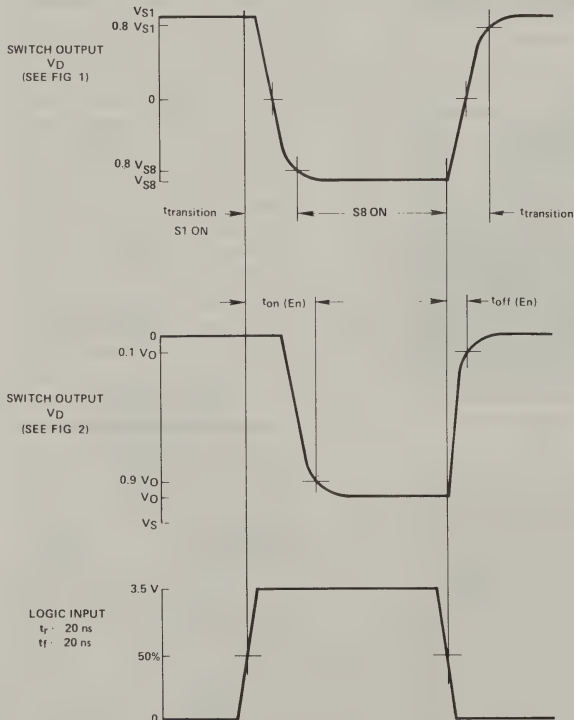


Figure 1(a)

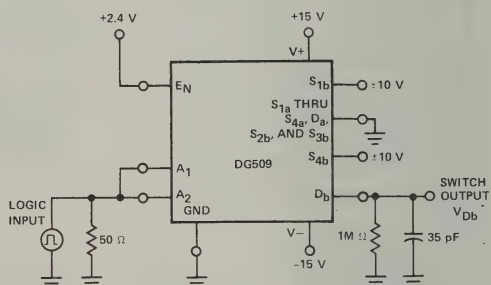


Figure 1(b)

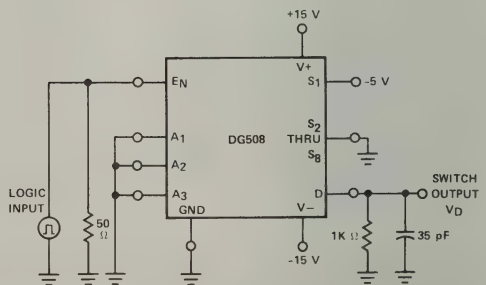


Figure 2



V+	V-	V <sub>IN</sub> Logic Input Voltage V <sub>INH</sub> Min/ V <sub>INL</sub> Max (V)	V <sub>S</sub> or V <sub>D</sub> Analog Voltage Range (V)
+15**	-15	2.4/0.8	-15 to +15
+12	-12	2.4/0.8	-12 to +12
+10	-10	2.4/0.6	-10 to +10
+8***	-8	2.4/0.4	-8 to +8

\*Application Hints are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

\*\*Electrical Characteristics chart based on V+ = +15 V, V- = -15 V.

\*\*\*Operation below ±8 V is not recommended due to the shift in V<sub>INL</sub>(MAX).

### Logic Inputs

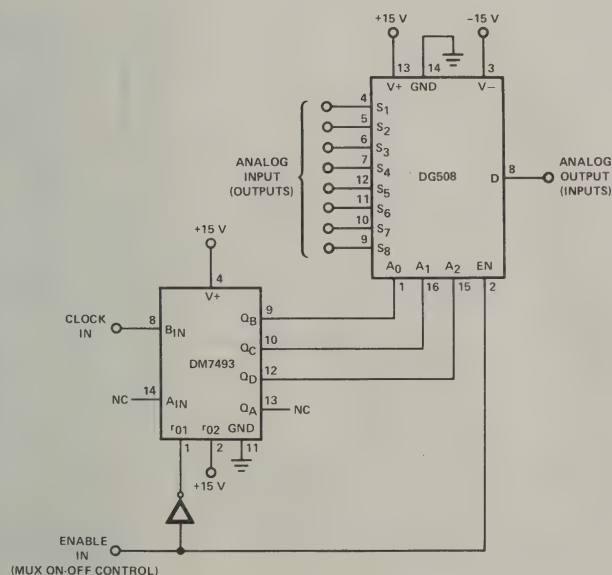
Logic input circuitry protects the input MOS gate from static transients. A series MOS device shuts off when V<sub>IN</sub> exceeds the positive power supply. Negative transients are clamped to ground by a diode clamp.

The input voltage characteristics have a current spike occurring at the transition voltage when the logic goes from V<sub>INH</sub> to V<sub>INL</sub>. If a series resistor is used for additional static protection, it should be limited to less than 9.1K Ω to insure switching with worst case current spikes.

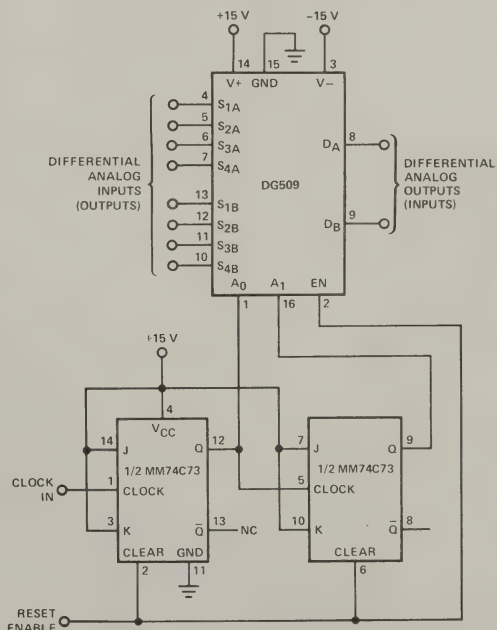
Truth Table

	ENABLE	MUX SEQUENCE RATE	MUX INPUTS			DG508 SWITCH PAIR STATES (- DENOTES OFF)							
			A <sub>0</sub>	A <sub>1</sub>	A <sub>2</sub>	S1	S2	S3	S4	S5	S6	S7	S8
DG508	0	0	X	X	X	-	-	-	-	-	-	-	-
	1	0	0	0	0	ON	-	-	-	-	-	-	-
	1	1 pulse	1	0	0	-	ON	-	-	-	-	-	-
	1	2 pulses	0	1	0	-	-	ON	-	-	-	-	-
	1	3 pulses	1	1	0	-	-	-	ON	-	-	-	-
	1	4 pulses	0	0	1	-	-	-	-	ON	-	-	-
	1	5 pulses	1	0	1	-	-	-	-	-	ON	-	-
	1	6 pulses	0	1	1	-	-	-	-	-	-	ON	-
	1	7 pulses	1	1	1	-	-	-	-	-	-	-	ON
	1	8 pulses	0	0	0	ON	-	-	-	-	-	-	-

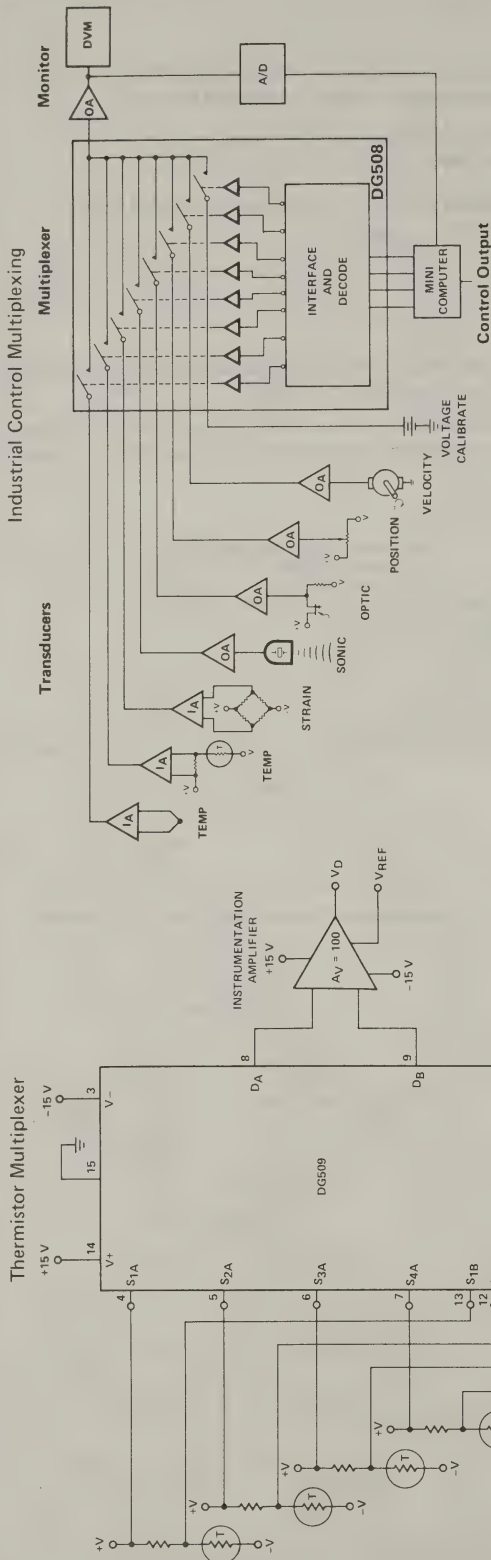
8 Channel Sequential Mux (Demux)



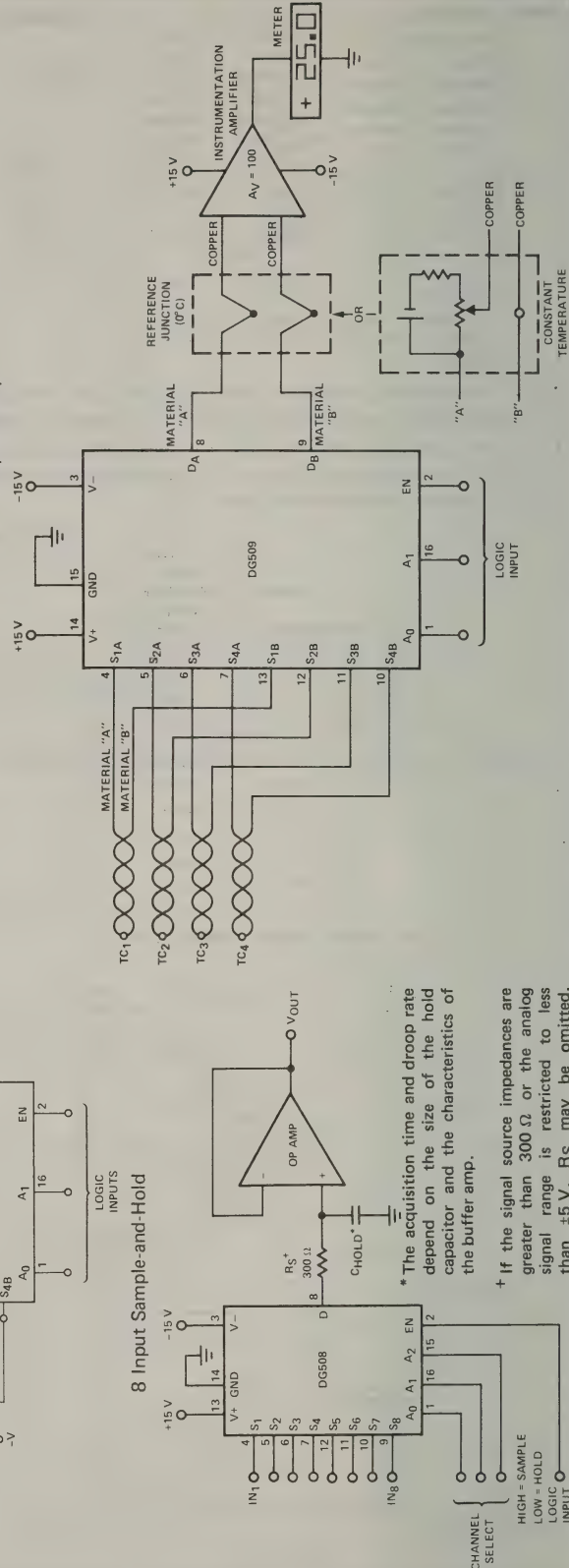
Differential 4 Channel Sequential Mux/Demux.



# APPLICATIONS (Cont'd)



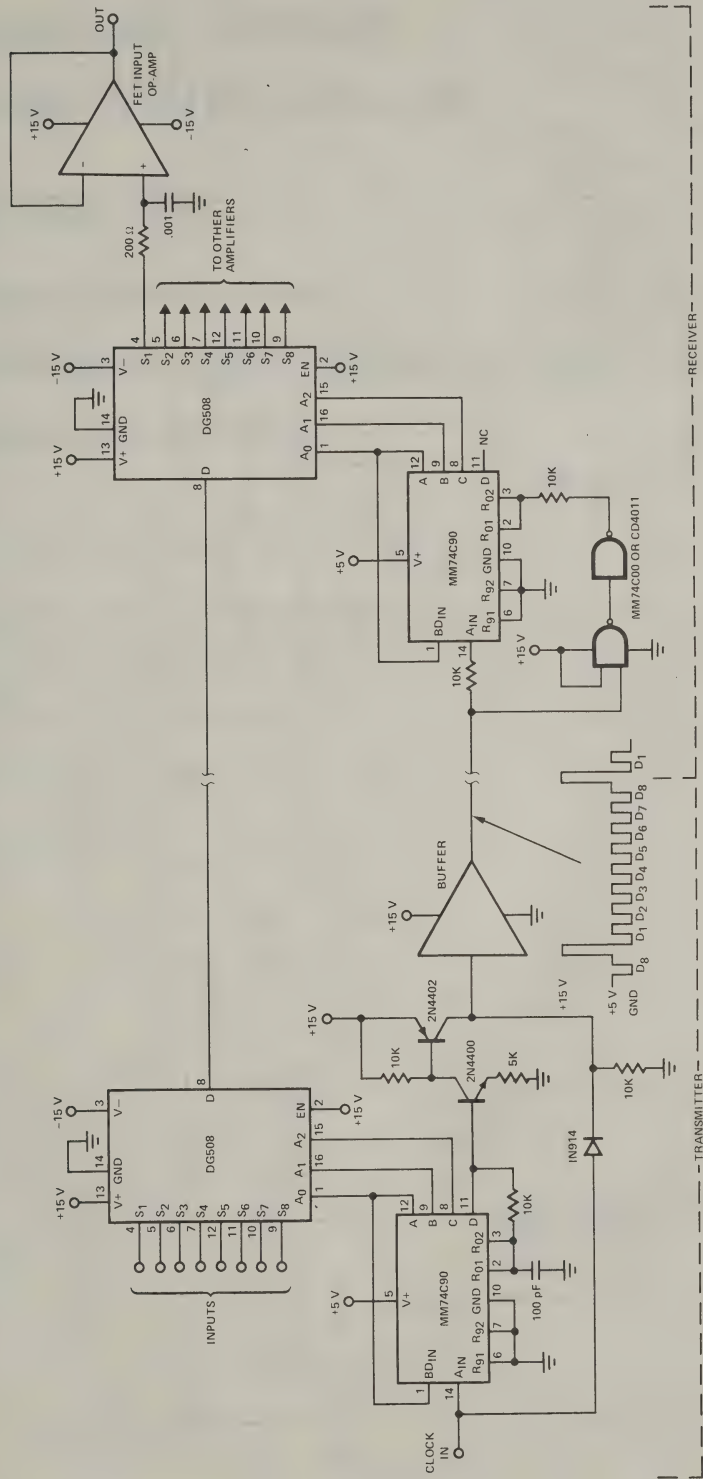
**DG509 Thermocouple Multiplexer**



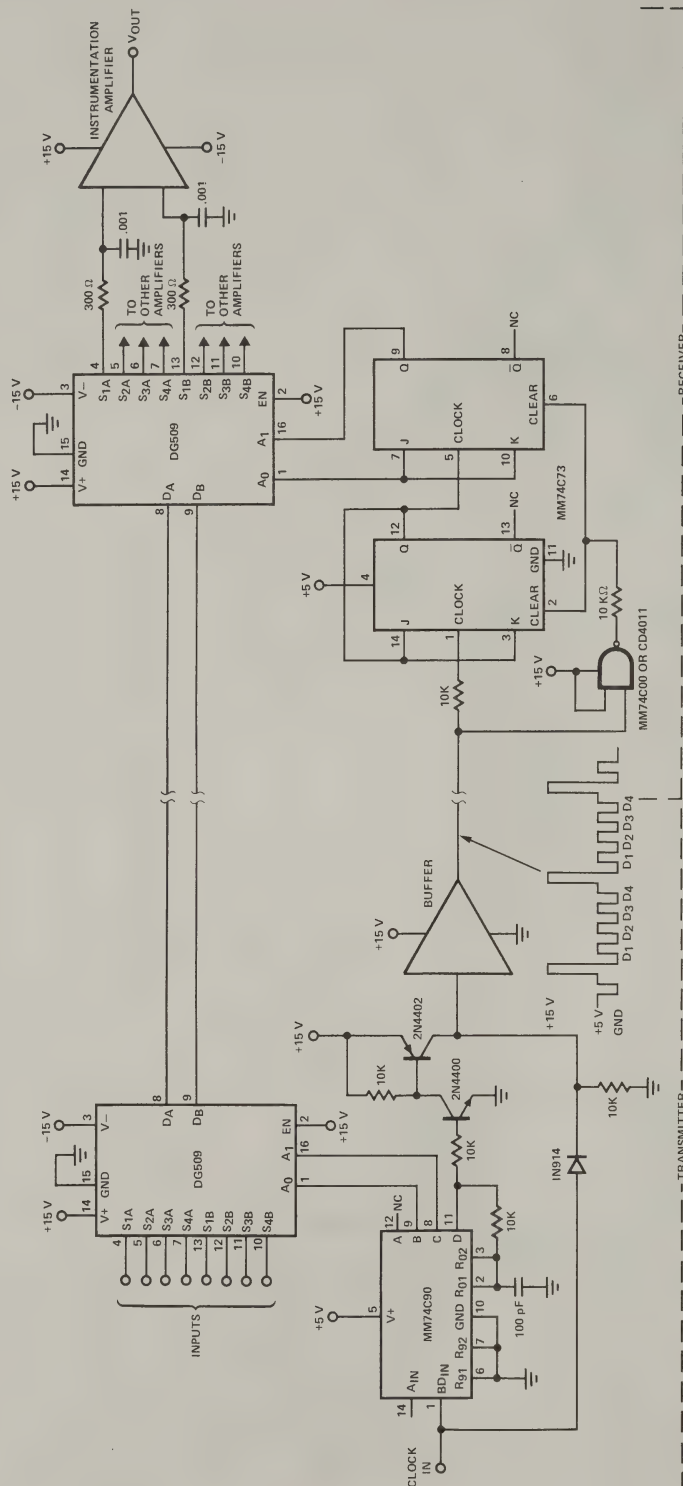
\* The acquisition time and droop rate depend on the size of the hold capacitor and the characteristics of the buffer amp.

+ If the signal source impedances are greater than 300Ω or the analog signal range is restricted to less than ±5V, RS may be omitted.

An 8 Channel Mux/Demux System



## Differential Mux/Demux System





# 8-Channel/Dual 4-Channel CMOS Analog Multiplexer



*designed for...*

- Data Acquisition Systems
- Multiplexing Reference Signals
- Communication Systems

## BENEFITS

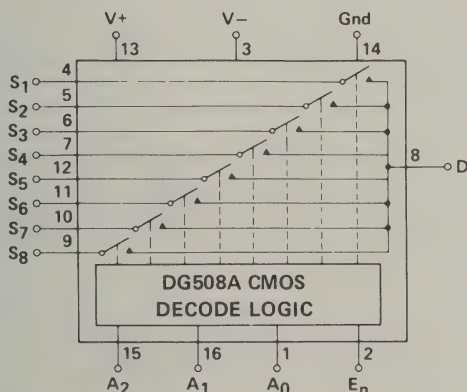
- Easily Interfaced
  - TTL, DTL and CMOS Direct Control Over Military Temperature Range
- Low Power
  - 30 mW Typical Quiescent Power
- Reduces System Cross-Talk
  - Break-Before-Make Switching Action
- Environmentally Rugged
  - Latchproof PLUS-40 CMOS
  - 44V Power Supply Maximum Rating
  - Static Protection Circuitry on all Inputs

## DESCRIPTION

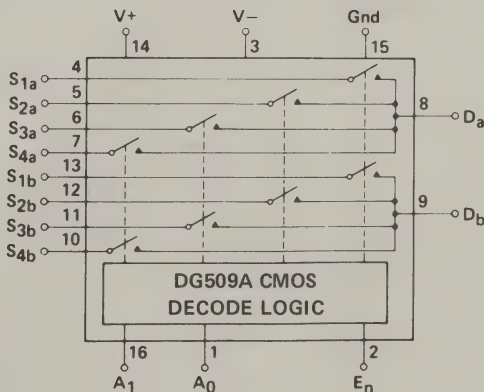
The DG508A a single ended 8 channel analog multiplexer connects 1 of 8 inputs to a common output decoded from 3 binary inputs ( $A_0$ ,  $A_1$ ,  $A_2$ ).

The DG509A a differential input 4 channel analog multiplexer connects 1 of 4 differential inputs to a common differential output decoded from 2 binary inputs ( $A_0$ ,  $A_1$ ). In the ON state each switch conducts current in either direction, and in the OFF state blocks voltage up to the power supply rails, generally 30 volts peak-to-peak. Bidirectional current switching also insures equal operation as a demultiplexer. An enable ( $E_n$ ) input provides a package select function. All control inputs address ( $A_n$ ) and enable ( $E_n$ ) are TTL or CMOS compatible over the full operating temperature range of the product. The multiplexers operate in a Break-Before-Make (BBM) switch action between any two decoded switch selections protecting against momentary shorting of the input transducers. Additionally BBM action occurs between package selection. See the DG528 and DG529 for the same function plus latches on the  $A_2$ ,  $A_1$ ,  $A_0$ ,  $E_n$  inputs.

## FUNCTIONAL DIAGRAMS



DG508A  
8 Channel Single Ended  
Multiplexer



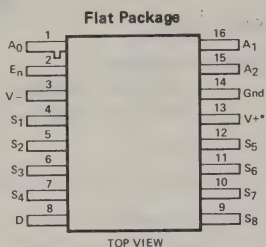
DG509A  
Differential 4 Channel  
Multiplexer

DG508A DG509A

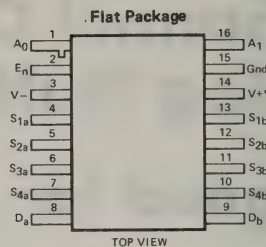
4

Analog Multiplexers

# PIN CONFIGURATIONS

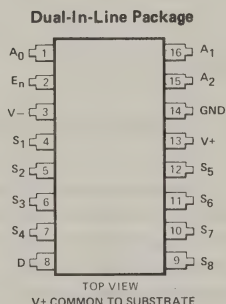


ORDER NUMBER:  
DG508AAL  
SEE PACKAGE 17

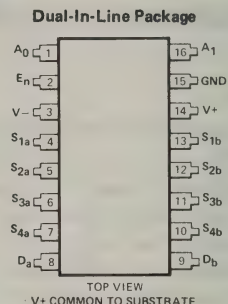


ORDER NUMBER:  
DG509AAL  
SEE PACKAGE 17

\*Common to Substrate and Base of Package



ORDER NUMBERS:  
DG508AAK, DG508ABK or DG508ACJ  
SEE PACKAGE 10  
SEE PACKAGE 8



ORDER NUMBERS:  
DG509AAK, DG509ABK or DG509ACK  
SEE PACKAGE 10  
SEE PACKAGE 8

## TRUTH TABLES

DG508A

A <sub>2</sub>	A <sub>1</sub>	A <sub>0</sub>	En	ON SWITCH
X	X	X	0	NONE
0	0	0	1	1
0	0	1	1	2
0	1	0	1	3
0	1	1	1	4
1	0	0	1	5
1	0	1	1	6
1	1	0	1	7
1	1	1	1	8

DG509A

A <sub>1</sub>	A <sub>0</sub>	En	ON SWITCH
X	X	0	NONE
0	0	1	1
0	1	1	2
1	0	1	3
1	1	1	4

Logic "0" = V<sub>AL</sub> ≤ 0.8V, Logic "1" = V<sub>AH</sub> ≥ 2.4V

# ABSOLUTE MAXIMUM RATINGS

Voltages referenced to V-

V+ . . . . . 44 V

GND. . . . . 25 V

Digital inputs<sup>4</sup>, V<sub>S</sub>, V<sub>D</sub> . . . . . -2 V to (V<sup>+</sup> + 2 V) or 20 mA, whichever occurs first.

Current (Any Terminal, Except S or D) . . . . . 30 mA

Continuous Current, S or D . . . . . 20 mA

Peak Current, S or D

(Pulsed at 1 msec, 10% Duty Cycle Max) . . . . . 40 mA

Operating Temperature (A Suffix) . . . . . -55 to 125°C

(B Suffix) . . . . . -20 to 85°C

(C Suffix) . . . . . 0 to 70°C

Storage Temperature (A & B Suffix) . . . . . -65 to 150°C

(C Suffix) . . . . . -65 to 125°C

Power Dissipation (Package)\*

16 Pin DIP\*\* . . . . . 900 mW

16 Pin Plastic DIP\*\*\* . . . . . 470 mW

Flat Package\*\*\*\* . . . . . 750 mW

\* All leads soldered or welded to PC board.

\*\* Derate 12 mW/°C above 75°C

\*\*\* Derate 6.3 mW/°C above 25°C

\*\*\*\* Derate 10 mW/°C above 75°C

# ELECTRICAL CHARACTERISTICS

All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC			MEASURED TERMINAL	NO. TESTS PER TEMP.	TYP <sup>1</sup> 25°C	MAX LIMITS					UNIT	TEST CONDITIONS, UNLESS NOTED: V <sub>+</sub> = 15 V, V <sub>-</sub> = 15 V, Ground = 0			
						A SUFFIX			B/C SUFFIXES						
						-55°C	25°C	125°C	-20/0°C	25°C	85/70°C				
1	SWITCH	V <sub>ANALOG</sub> Minimum Analog Signal Handling Capability			±15		±15	±15		±15	±15	V			
2		r <sub>DS(on)</sub> Drain-Source ON-Resistance	S to D	8	270	400	400	500	450	450	550	Ω	V <sub>D</sub> = 10 V, I <sub>S</sub> = -200 μA	Sequence each switch on	
3				8	230	400	400	500	450	450	500	V <sub>D</sub> = -10 V, I <sub>S</sub> = -200 μA	V <sub>AL</sub> = 0.8 V, V <sub>AH</sub> = 2.4 V		
4		Δr <sub>DS(on)</sub> Greatest Change in Drain Source ON Resistance Between Channels	S to D	8	6							%	$\Delta r_{DS(on)} = \left( \frac{r_{DS(on) \text{ MAX}} - r_{DS(on) \text{ MIN}}}{r_{DS(on) \text{ AVE}}} \right)$ -10 V < V <sub>S</sub> < 10 V		
5		SWITCH	I <sub>S(off)</sub> Source OFF Leakage Current	S	8	0.002		±1	±50		±5	±50	V <sub>S</sub> = 10 V, V <sub>D</sub> = -10 V	V <sub>EN</sub> = 0	
6					8	-0.005		±1	±50		±5	±50	V <sub>S</sub> = -10 V, V <sub>D</sub> = 10 V		
7			I <sub>D(off)</sub> Drain OFF Leakage Current	DG508A	D	1	0.010		±10	±200		±20	±200		V <sub>D</sub> = 10 V, V <sub>S</sub> = -10 V
8						1	-0.015		±10	±200		±20	±200		V <sub>D</sub> = -10 V, V <sub>S</sub> = 10 V
9				DG509A		2	0.005		±10	±100		±20	±100		V <sub>D</sub> = 10 V, V <sub>S</sub> = -10 V
10						2	-0.008		±10	±100		±20	±100		V <sub>D</sub> = -10 V, V <sub>S</sub> = 10 V
11			I <sub>D(on)</sub> <sup>2</sup> Drain ON Leakage Current	DG508A	D	8	0.015		±10	±200		±20	±200	V <sub>S(alt)</sub> = V <sub>D</sub> = 10 V	Sequence each switch on V <sub>AL</sub> = 0.8 V, V <sub>AH</sub> = 2.4 V
12						8	-0.030		±10	±200		±20	±200	V <sub>S(alt)</sub> = V <sub>D</sub> = -10 V	
13				DG509A		8	0.007		±10	±100		±20	±100	V <sub>S(alt)</sub> = V <sub>D</sub> = 10 V	
14						8	-0.015		±10	±100		±20	±100	V <sub>S(alt)</sub> = V <sub>D</sub> = -10 V	
15	INPUT	I <sub>AH</sub> Address Input Current, Input Voltage High	A <sub>0</sub> , A <sub>1</sub> , (A <sub>2</sub> ), EN	(4) 3	-0.002		±10	-30		-10	-30	V <sub>A</sub> = 2.4 V	All V <sub>A</sub> = 0		
16				(4) 3	0.006		10	30		10	30	V <sub>A</sub> = 15 V			
17		I <sub>AL</sub> Address Input Current Input Voltage Low		(3) 2	-0.002		-10	-30		-10	-30	V <sub>EN</sub> = 2.4 V			
18				1	-0.002		-10	-30		-10	-30	V <sub>EN</sub> = 0			
19	DYNAMIC	t <sub>transition</sub> Switching Time of Multiplexer	D	1	0.6		1					See Figure 1			
20		t <sub>open</sub> Break-Before-Make Interval	D		0.2							See Figure 3			
21		t <sub>on(EN)</sub> Enable Turn-ON Time	D	1	1.0		1.5					See Figure 2			
22		t <sub>off(EN)</sub> Enable Turn-OFF Time	D	1	0.4		1								
23		MISC	OIRR OFF Isolation (Note 3)	D	8	68							V <sub>EN</sub> = 0, R <sub>L</sub> = 1 K Ω, C <sub>L</sub> = 15 pF V <sub>S</sub> = 7 V <sub>RMS</sub> , f = 500 kHz		
24			C <sub>S(off)</sub> Source OFF Capacitance	S	8	5							V <sub>S</sub> = 0	V <sub>EN</sub> = 0, f = 140 kHz	
25	C <sub>D(off)</sub> Drain OFF Capacitance		DG508A	D	1	25						V <sub>D</sub> = 0			
26			DG509A	D	2	12									
27	SUPPLY	I <sub>+</sub> Positive Supply Current	V <sub>+</sub>	1	1.3		2.4			2.4		V <sub>EN</sub> = 2.4 V	All V <sub>A</sub> = 0, or 2.4 V		
28		I <sub>-</sub> Negative Supply Current	V <sub>-</sub>	1	-0.7		-1.5			-1.5		V <sub>EN</sub> = 0 V			
29		I <sub>+</sub> Standby Positive Supply Current	V <sub>+</sub>	1	1.3		2.4			2.4					
30		I <sub>-</sub> Standby Negative Supply Current	V <sub>-</sub>	1	-0.7		-1.5			-1.5					

## NOTES:

- Typical Values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.
- I<sub>D(on)</sub> is leakage from driver into "ON" switch.
- OFF isolation = 20 log  $\frac{|V_S|}{|V_D|}$ , V<sub>S</sub> = input to "OFF" switch, V<sub>D</sub> = output due to V<sub>S</sub>.
- Signals on S<sub>X</sub>, D<sub>X</sub> or I<sub>NX</sub> exceeding V<sup>+</sup> or V<sup>-</sup> will be clamped by internal diodes. Limit forward diode current to maximum current ratings.

ICMG-A DG508A  
ICMG-B DG509A

# SWITCHING TIME TEST CIRCUIT

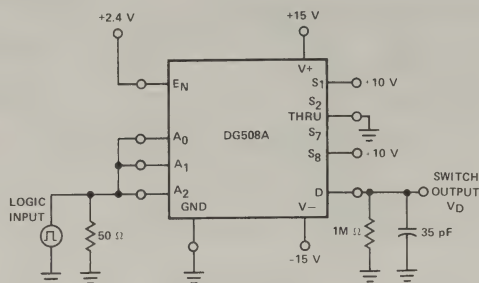


Figure 1(a)

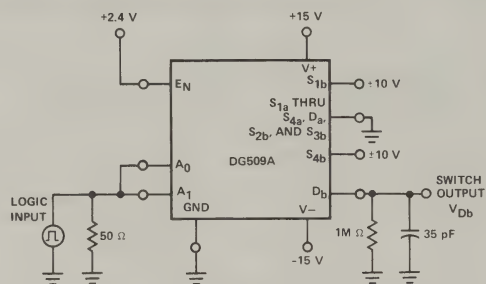


Figure 1(b)

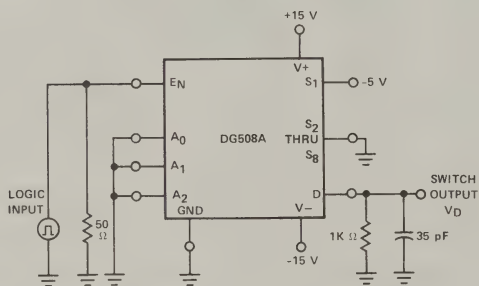


Figure 2(a)

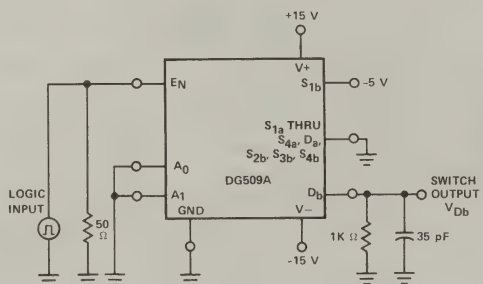


Figure 2(b)

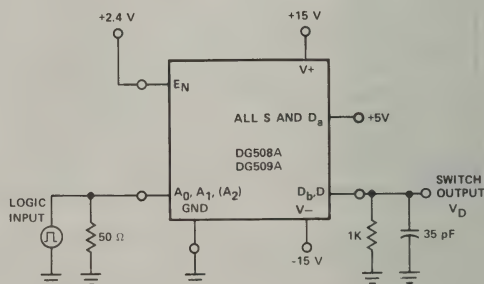
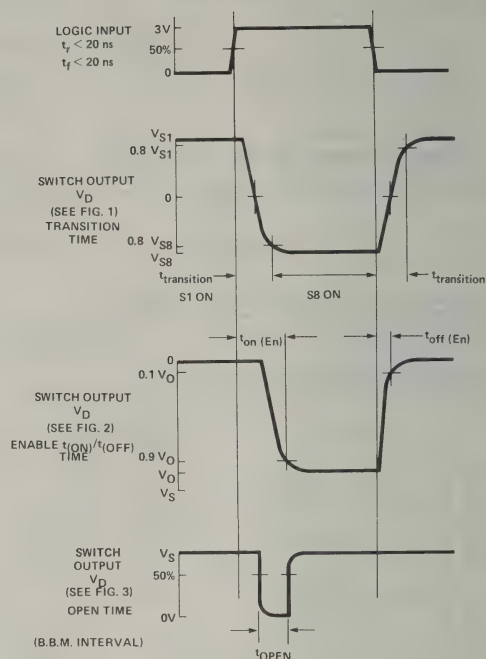


Figure 3



# 8-Channel and Dual 4-Channel Latchable Multiplexers designed for . . .

- Data Acquisition Systems
- Automatic Test Equipment
- Communication Systems
- Microprocessor Controlled Systems

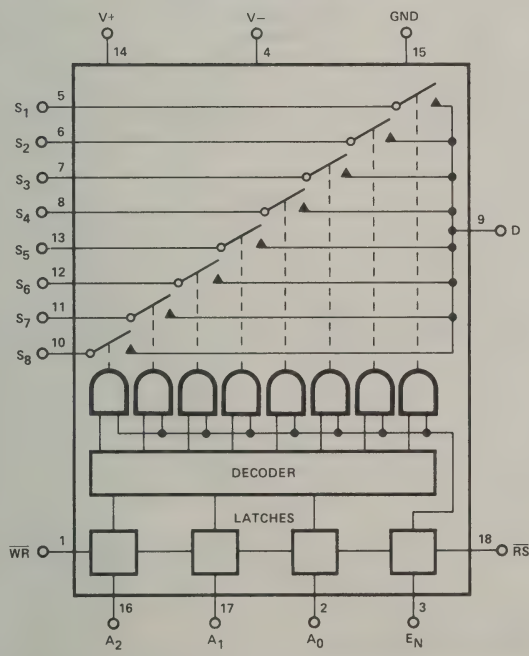
## DESCRIPTION

The DG528 and DG529 designed on the Siliconix PLUS-40 CMOS Process provides solid state switch action with 400 ohms contact (ON) resistance and very high OFF resistance. True bidirectional switch action takes place over the full analog signal range of  $\pm 15$  volts, with break-before-make operation to prevent momentary shorting of signal inputs. The DG528 provides 8-channel single-ended multiplexing and demultiplexing of  $\pm 15$  volt analog signals. The DG529 provides 4-channel differential multiplexing and demultiplexing of  $\pm 15$  volt common mode plus differential mode signals.

Four input latches on the binary coded switch-state inputs ( $A_0$ ,  $A_1$ ,  $A_2$ ,  $E_N$ ) result in microprocessor bus compatibility. Two control lines,  $\overline{WR}$  and  $\overline{RS}$ , store or clear the the switch-state input ( $A_0$ ,  $A_1$ ,  $A_2$ ,  $E_N$ ) latches. Programming the enable input ( $E_N$ ) latch with a logic zero turns all analog switches OFF. The direct chip reset  $\overline{RS}$  simplifies switch turn OFF during system power up or system reset.

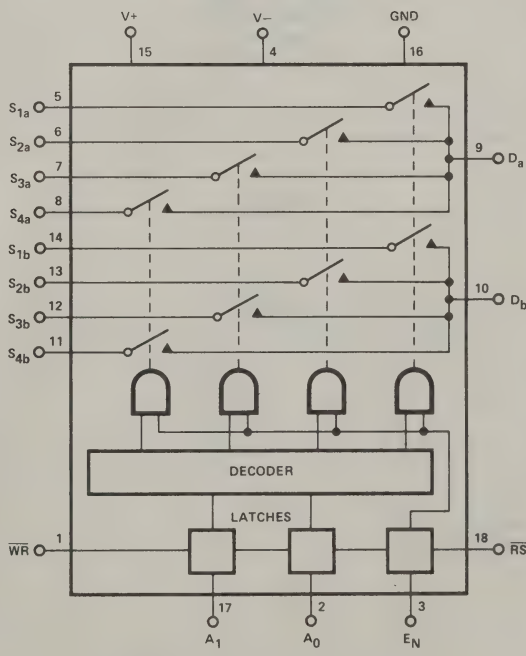
## FUNCTIONAL DIAGRAMS

DG528



8 Channel Single Ended Multiplexer

DG529



Differential 4 Channel Multiplexer

## BENEFITS

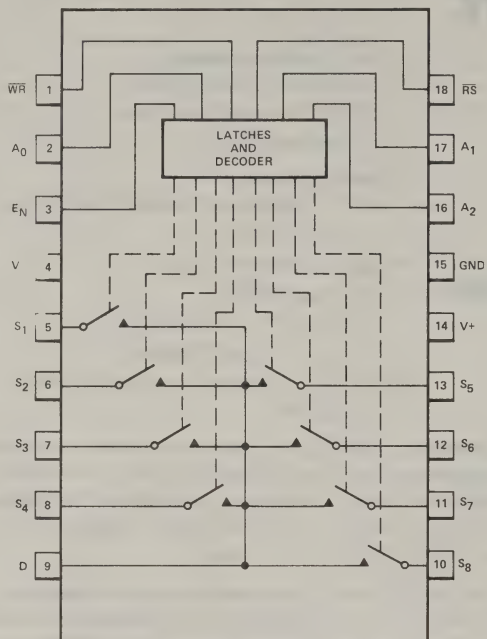


- Microprocessor Bus Compatible
  - Accepts 300 nsec WRITE Pulse Width
  - Direct RESET
- Environmentally Rugged
  - 44V Power Supply Rating
  - Static Protected Logic Inputs
  - Latch-Proof
- Easily Interfaced
  - TTL Compatible Without Pullup Resistors  
 $V_{INH} = 2.4V$
- Improved System Accuracy
  - $r_{DS(on)} < 400\Omega$
  - $V_{error} = 80 \mu V \text{ Max at } 125^\circ C$   
 $= I_{D(on)} \times r_{DS(on)}$
  - $\Delta r_{DS(on)}$  Channel to Channel is Less Than 6%

# PIN CONFIGURATIONS

## DG528

Dual-In-Line Package

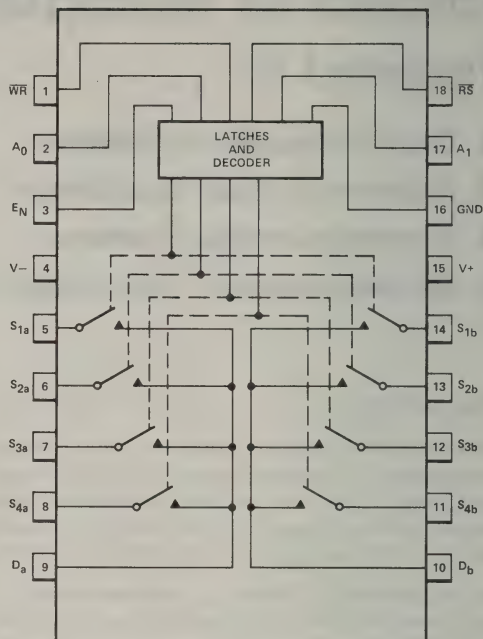


Top View

ORDER NUMBERS:  
DG528AK OR DG528BK  
SEE PACKAGE 23  
DG528CJ  
SEE PACKAGE 19

## DG529

Dual-In-Line Package



Top View

ORDER NUMBERS:  
DG529AK OR DG529BK  
SEE PACKAGE 23  
DG529CJ  
SEE PACKAGE 19

# TRUTH TABLES

## DG528

A <sub>2</sub>	A <sub>1</sub>	A <sub>0</sub>	E <sub>n</sub>	WR	RS	On Switch
X	X	X	X		1	Maintains previous switch condition
X	X	X	X	X	0	NONE (latches cleared)
X	X	X	0	0	1	NONE
0	0	0	1	0	1	1
0	0	1	1	0	1	2
0	1	0	1	0	1	3
0	1	1	1	0	1	4
1	0	0	1	0	1	5
1	0	1	1	0	1	6
1	1	0	1	0	1	7
1	1	1	1	0	1	8

## DG529

A <sub>1</sub>	A <sub>0</sub>	E <sub>n</sub>	WR	RS	On Switch
X	X	X		1	Maintains previous switch condition
X	X	X	X	0	NONE (latches cleared)
X	X	0	0	1	NONE
0	0	1	0	1	1
0	1	1	0	1	2
1	0	1	0	1	3
1	1	1	0	1	4

Logic "1": V<sub>AH</sub> ≥ 2.4V

Logic "0": V<sub>AL</sub> ≤ 0.8V

# ABSOLUTE MAXIMUM RATINGS (T<sub>A</sub> = 25°C unless otherwise noted)

Voltages referenced to V-

V<sup>+</sup> ..... 44 V  
GND. .... 25 V  
Digital inputs<sup>5</sup>, V<sub>S</sub>, V<sub>D</sub> ..... -2 V to (V<sup>+</sup> +2 V) or  
20 mA, whichever occurs first.

Current (Any Terminal Except S or D) .... 30 mA  
Continuous Current, S or D ..... 20 mA  
Peak Current, S or D  
(Pulsed at 1 msec, 10% Duty Cycle Max) . 40 mA

Operating Temperature (A Suffix) -55 to 125°C  
(B Suffix) -20 to 85°C  
(C Suffix) 0 to 70°C  
Storage Temperature (A & B Suffix) -65 to 150°C  
(C Suffix) -65 to 125°C  
Power Dissipation (Package)\*  
18 Pin DIP\*\* ..... 900 mW  
18 Pin Plastic DIP\*\*\* ..... 470 mW

\*All leads soldered or welded to PC board.

\*\*Derate 12 mW/°C above 75°C.

\*\*\*Derate 6.3 mW/°C above 50°C

**ELECTRICAL CHARACTERISTICS** All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

Characteristic			Measured Terminal	No. Tests Per Temp.	Typ 25°C Note 1	Max Limits						Unit	Test Conditions, Unless Noted: V <sup>+</sup> = 15, V <sup>-</sup> = -15, Ground = 0 WR = 0, RS = 2.4V			
						A Suffix			B/C Suffixes							
						-55°C	25°C	125°C	-20°C 0°C	25°C	85°C					
1	V <sub>ANALOG</sub>	Minimum Analog Signal Handling Capability			±15		±15	±15		±15	±15	V				
2	r <sub>DS(on)</sub>	Drain-Source ON Resistance	S to D	8	270	400	400	500	450	450	550	Ω	V <sub>D</sub> = 10V, I <sub>S</sub> = -200 μA	Sequence each switch on		
3				8	230	400	400	500	450	450	500		V <sub>D</sub> = -10V, I <sub>S</sub> = -200 μA	V <sub>AL</sub> = 0.8V, V <sub>AH</sub> = 2.4V		
4	Δr <sub>DS(on)</sub>	Greatest Change in Drain Source ON Resistance Between Channels	S to D	8	6							%	$\Delta r_{DS(on)} = \left( \frac{r_{DS(on)}^{MAX} - r_{DS(on)}^{MIN}}{r_{DS(on)}^{AVE}} \right)$ -10V < V <sub>S</sub> < 10V			
5	I <sub>S(off)</sub>	Source OFF Leakage Current	S	8	-0.005		±1	±50		±5	±50		V <sub>S</sub> = 10V, V <sub>D</sub> = -10V	V <sub>EN</sub> = 0		
6				8	-0.005		±1	±50		±5	±50		V <sub>S</sub> = -10V, V <sub>D</sub> = 10V			
7	I <sub>D(off)</sub>	Drain OFF Leakage Current	D	1	-0.015		±10	±200		±20	±200		V <sub>D</sub> = 10V, V <sub>S</sub> = -10V			
8						1	-0.015		±10	±200		±20	±200			V <sub>D</sub> = -10V, V <sub>S</sub> = 10V
9						2	-0.008		±10	±100		±20	±100		V <sub>D</sub> = 10V, V <sub>S</sub> = -10V	
10	I <sub>D(on)</sub>	Drain ON Leakage Current Note 2	D	2	-0.008		±10	±100		±20	±100	nA	V <sub>D</sub> = -10, V <sub>S</sub> = 10V	Sequence each switch on V <sub>AL</sub> = 0.8V, V <sub>AH</sub> = 2.4V		
11						8	-0.03		±10	±200		±20	±200			V <sub>S</sub> (all) = V <sub>D</sub> = 10V
12						8	-0.03		±10	±200		±20	±200			V <sub>S</sub> (all) = V <sub>D</sub> = -10V
13			8	-0.015		±10	±100		±20	±100		V <sub>S</sub> (all) = V <sub>D</sub> = 10V				
14				8	-0.015		±10	±100		±20	±100		V <sub>S</sub> (all) = V <sub>D</sub> = -10V			
15	I <sub>AH</sub>	Logic Input Current, Input Voltage High	A <sub>0</sub> , A <sub>1</sub> , (A <sub>2</sub> ), E <sub>n</sub> , WR, RS	5 (6)	-0.002		±10	-30		-10	-30	μA	V <sub>A</sub> = 2.4V			
16	I <sub>AL</sub>	Logic Input Current, Input Voltage Low		5 (6)	0.006		10	30		10	30		V <sub>A</sub> = 15V			
17	t <sub>transition</sub>	Switching Time of Multiplexer	D	1	0.6		1						V <sub>EN</sub> = 0	All V <sub>A</sub> = 0, WR = 0, RS = 0		
18	t <sub>open</sub>	Break-Before-Make Interval	D		0.2											
19	t <sub>on</sub> (EN, WR)	Enable Turn-ON Time	D	1	1.0		1					μs	See Figure 3			
20	t <sub>off</sub> (EN, RS)	Enable and RS Reset Turn-OFF Time	D	1	0.4		1						See Figure 5			
21	Q	Charge Coupling	D		4.0								See Figures 4 and 6			
22	OFF Isolation	Note 3	D	8	68							pC	See Figure 4 and 7			
23	C <sub>in</sub>	Logic Input Capacitance	A <sub>0</sub> , A <sub>1</sub> , (A <sub>2</sub> ) E <sub>n</sub> , WR, RS		2.5								See Figure 8			
24	C <sub>S(off)</sub>	Source OFF Capacitance	S	8	5							pF	V <sub>EN</sub> = 0, R <sub>L</sub> = 1KΩ, C <sub>L</sub> = 15 pF V <sub>S</sub> = 7 VRMS, f = 500 kHz			
25	C <sub>D(off)</sub>	Drain OFF Capacitance	DG528	D	1	25							V <sub>S</sub> = 0	V <sub>EN</sub> = 0, f = 140 kHz		
26			DG529	D	2	12									V <sub>D</sub> = 0	
27	I <sup>+</sup>	Positive Supply Current	V <sup>+</sup>	1			2.5			2.5		mA	V <sub>EN</sub> = 0V	All V <sub>A</sub> = 0		
28	I <sup>-</sup>	Negative Supply Current	V <sup>-</sup>	1			-1.5			-1.5						
29																

## NOTES:

- Typical Values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.
- I<sub>D(on)</sub> is leakage from driver into "ON" switch.
- OFF isolation = 20 log |V<sub>S</sub>|, V<sub>S</sub> = input to "OFF" switch, V<sub>D</sub> = output due to V<sub>S</sub>. |V<sub>D</sub>|
- Period of Reset (RS) pulse must be at least 50 μsec during or after power ON.
- Signals on S<sub>X</sub>, D<sub>X</sub> or I<sub>NX</sub> exceeding V<sup>+</sup> or V<sup>-</sup> will be clamped by internal diodes. Limit forward diode current to maximum current ratings.

ICML-A DG528  
ICML-B DG529

# TIMING DIAGRAMS

## Minimum Input Timing Requirements

	Parameter	Measured Terminal	Min Limits over full temp range	Unit	Test Circuit
30	$t_{WW}$ WRITE Pulse Width	$\overline{WR}$	300	ns	See Figure 1
31	$t_{Dw}$ A, $E_n$ Data Valid to WRITE (Stabilization Time)	$A_0, A_1, (A_2), E_n$ $\overline{WR}$	180		
32	$t_{WD}$ A, $E_n$ Data Valid after WRITE (Hold Time)	$\overline{WR}$ $A_0, A_1, (A_2), E_n$	30		
33	$t_{RS}$ RESET Pulse Width Note 4	$\overline{RS}$	500		See Figure 2 $V_S = 5V$

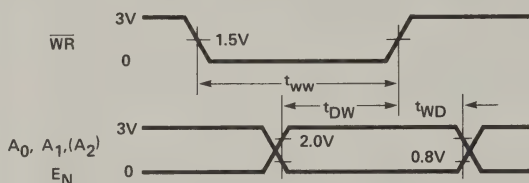


Figure 1.

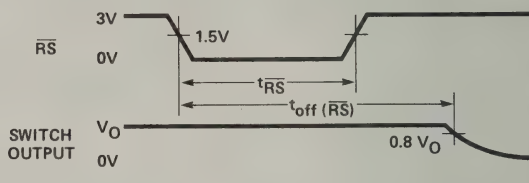
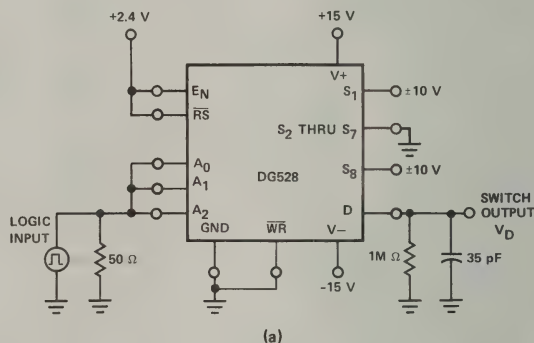
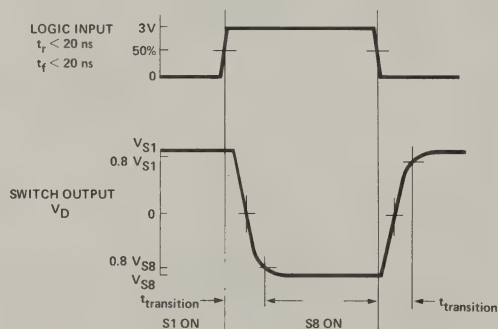
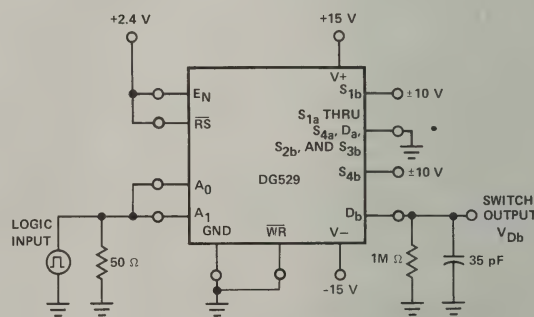


Figure 2.

## SWITCHING TIME TEST CIRCUITS



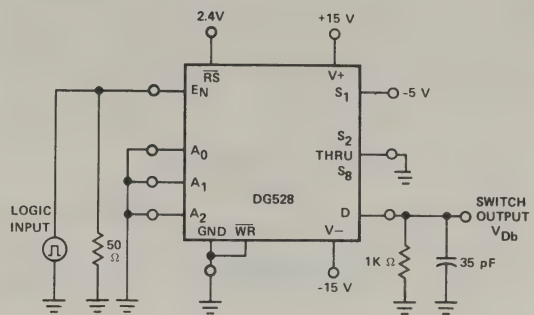
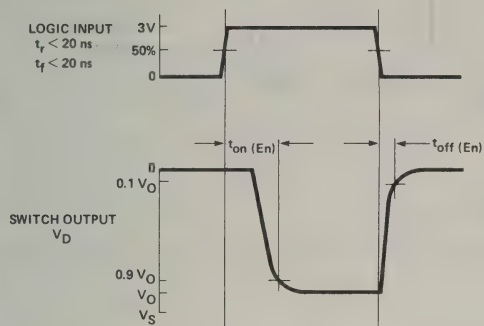
(a)



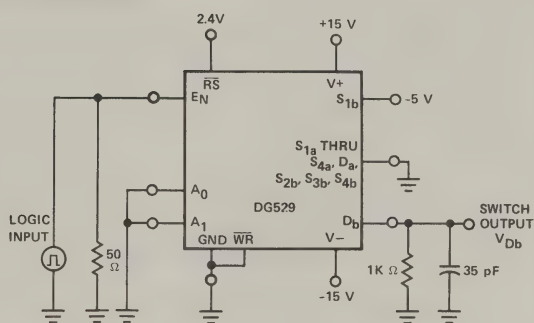
(b)

Figure 3. Transition Time Test Circuit





(a)



(b)

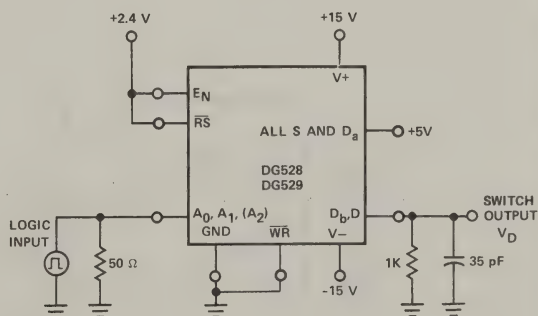
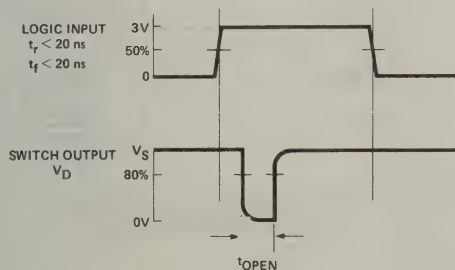
Figure 4. Enable  $t_{on}/t_{off}$  Time


Figure 5. Open Time (B.B.M. Interval)

# SWITCHING TIME TEST CIRCUITS (Cont'd)

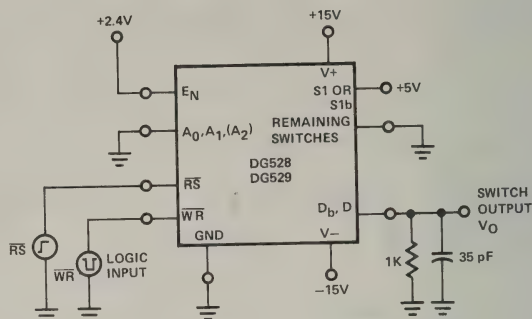
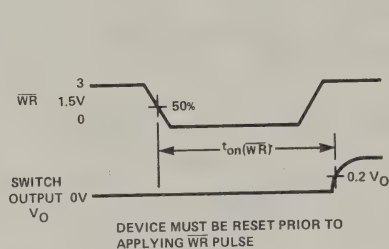


Figure 6. Write Turn-On Time  $t_{on}(WR)$

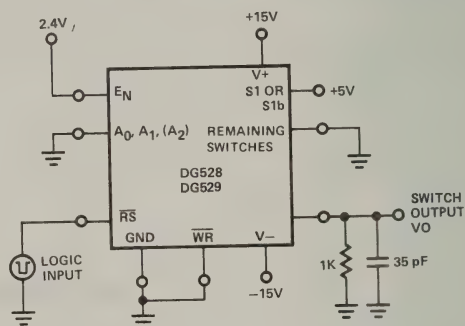
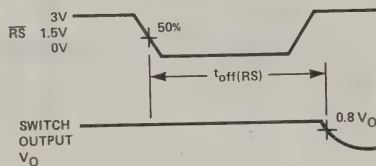


Figure 7. Reset Turn-Off Time  $t_{off}(RS)$

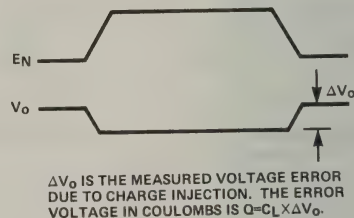
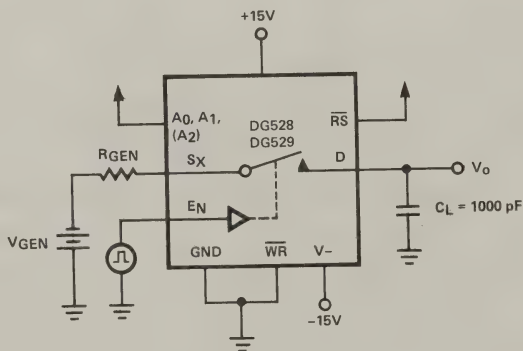


Figure 8. Charge Injection Test Circuit

The internal structure of the DG528 and DG529 provides a 5 volt logic interface with input protection circuitry followed by a latch, level shifter, decoder and finally the switch constructed with parallel N and P channel MOSFETs (see figure 9).

Looking at figure 9, the input protection on the logic lines  $A_0$ ,  $A_1$ ,  $A_2$ ,  $E_n$  and control lines  $\overline{WR}$ ,  $\overline{RS}$  minimize susceptibility to static encountered during handling and operational transients.

The logic interface circuit compares the TTL input signal against a TTL threshold reference voltage. The output of the comparator feeds the data input of a D-type latch. The level sensitive D latch continuously places the  $D_x$  input signal on the  $Q_x$  output when the CLK ( $\overline{WR}$ ) input is low, resulting in transparent operation. As soon as CLK ( $\overline{WR}$ ) returns high the latch holds the data last present on the  $D_x$  input at the  $Q_x$  output, subject to the "Minimum Input Timing Requirements" table.

Following the latches the  $Q_x$  signals are level shifted and decoded to provide proper drive levels for the CMOS switches. This level shifting insures full ON/OFF switch operation for any analog signal present between the  $V+$  and  $V-$  supply pins.

## Power Supplies

The final data sheet will provide graphs showing the effect on power supply sensitive parameters.

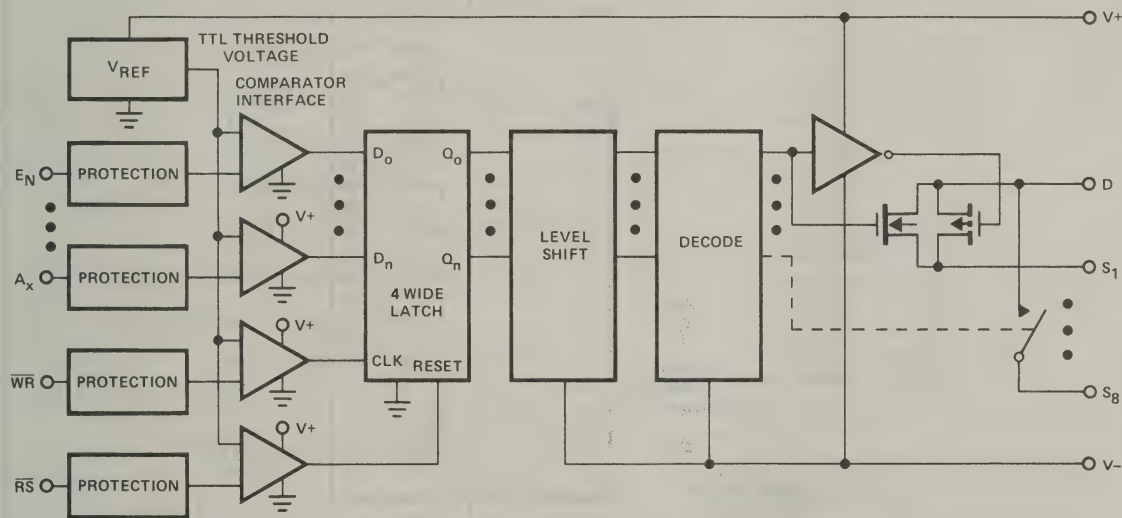


Figure 9. DG528 Simplified Internal Structure

# APPLICATIONS

The DG528 and DG529 minimize the amount of interface hardware between a microprocessor system bus and the analog system being controlled or measured. The internal TTL compatible latches give these multiplexers memory, that is, they can be programmed to stay in a particular switch state (e.g., switch 1 ON) until the microprocessor determines it is necessary to turn a different switch ON or turn all switches OFF.

The input latches become transparent when  $\overline{WR}$  is held low; therefore, these multiplexers operate by direct command of the coded switch state on  $A_2$ ,  $A_1$ ,  $A_0$ . In this mode the DG528 is identical to the very popular DG508 even sharing the same pin locations. The same is true of the DG529 versus the popular DG509.

## Circuit Operation: (See Figure 10)

Initially during system power-up  $\overline{RS}$  would be

active low maintaining all 8 switches in the OFF state. After  $\overline{RS}$  returned high the DG528 maintains all switches in the OFF state. As soon as the system program was ready to perform a write operation to the address assigned to the DG528, the address decoder would provide a  $\overline{CS}$  active low signal which is gated with the WRITE ( $\overline{WR}$ ) control signal. At this time the data on the DATA BUS (that will determine which switch to close) is stabilizing. When the  $\overline{WR}$  signal returns to the high state, (positive edge) the input latches of the DG528 save the data from the DATA bus. The coded information in the  $A_0$ ,  $A_1$ ,  $A_2$  and  $E_N$  latches is decoded and the appropriate switch is turned ON.

The  $E_N$  latch allows all switches to be turned OFF under program control. This becomes useful when two or more DG528s are cascaded to build 16-line and larger analog signal input multiplexers.

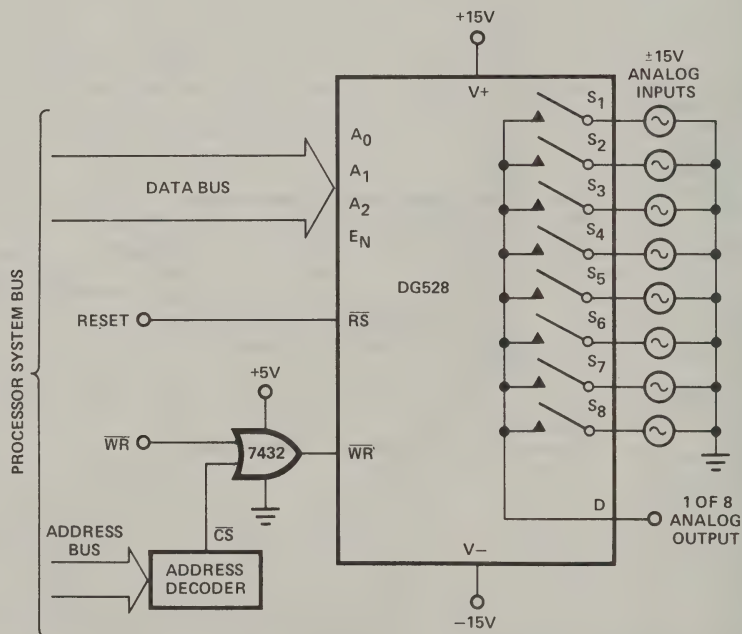


Figure 10



# Monolithic 8-Channel Multiplex Switch with Decode designed for . . .



Si3705

## ■ Multiplexing Analog Signals

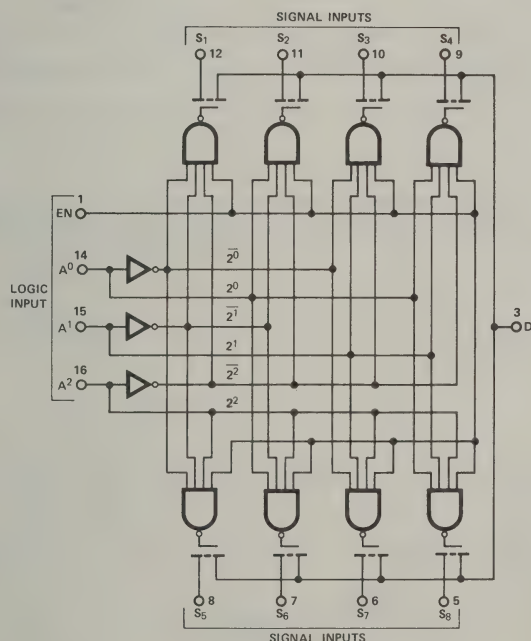
### BENEFITS

- Reduces External Component Requirements
  - On Board Decoding
  - Internal Zener Diodes Protect MOS Gates
- Minimizes Channel Cross-Talk Problems
  - Break-Before-Make Switching

### DESCRIPTION

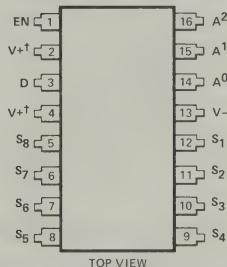
The Si3705 is designed to function as a single-pole, 8-position (plus OFF) electronic switch. The function is implemented by using eight P-channel MOS field-effect transistors as analog switches. In the ON state, each switch will conduct current equally well in either direction, and in the OFF state each switch will block voltages up to 5 V peak-to-peak. The ON-OFF state of each switch is controlled by drivers, which are in turn controlled by a 3-bit binary word plus an Enable-Inhibit input. The truth table shown below indicates the binary word required to select any one of the eight switch positions. Logic input levels "L" and "H" correspond to positive logic "0" and "1". Assuming supply voltages of 5 and -20 V, logic "L"  $\leq 0.6$  V and logic "H"  $\geq 3.5$  V. The rise and fall times of the drivers are designed to provide break-before-make switch action.

### FUNCTIONAL DIAGRAM



### PIN CONFIGURATION

Dual-In-Line Package



ORDER NUMBERS: Si3705142K, Si3705143K,  
Si3705192K OR Si3705193K  
SEE PACKAGE 10

ORDER NUMBER: Si3705192P  
SEE PACKAGE 12

† Both V+ lines are internally connected, either one or both may be used. V+ common to substrate.

### TRUTH TABLE

LOGIC INPUTS				CHANNEL
A <sup>0</sup>	A <sup>1</sup>	A <sup>2</sup>	En	'ON'
L	L	L	H	S <sub>1</sub>
H	L	L	H	S <sub>2</sub>
L	H	L	H	S <sub>3</sub>
H	H	L	H	S <sub>4</sub>
L	L	H	H	S <sub>5</sub>
H	L	H	H	S <sub>6</sub>
L	H	H	H	S <sub>7</sub>
H	H	H	H	S <sub>8</sub>
X	X	X	L	OFF

## ABSOLUTE MAXIMUM RATINGS

$V_+$ to $V_-$ .....	-0.3, 35 V
$V_+$ to $V_A$ , $V_{En}$ .....	-0.3, 35 V
$V_+$ to $V_D$ or $V_S$ .....	-0.3, 35 V
$V_D$ to $V_S$ .....	$\pm 25$ V
$V_A$ , $V_{En}$ to $V_-$ .....	35 V
$V_D$ or $V_S$ to $V_-$ .....	35 V

Current (Any Terminal) .....	-20 mA
Storage Temperature .....	-65 to 150°C
Operating Temperature (A Suffix) .....	-55 to 125°C
(C Suffix) .....	0 to 70°C

Power Dissipation\* .....

900 mW  
\*All leads soldered or welded to PC board. Derate 12 mW/°C above 75°C

## ELECTRICAL CHARACTERISTICS

All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

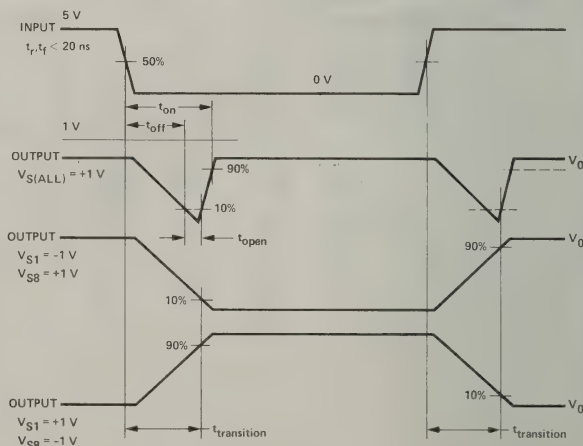
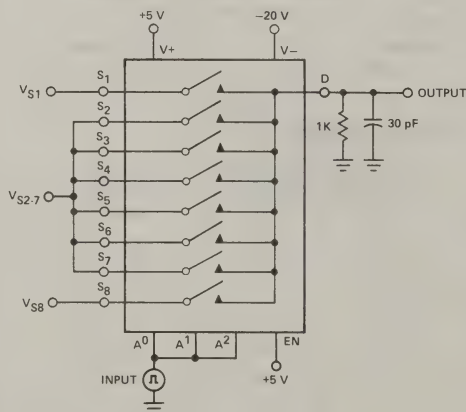
CHARACTERISTIC				MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V <sub>-</sub> = -20 V, V <sub>+</sub> = 5 V, V <sub>En</sub> = 3.5 V V <sub>AL</sub> = 0.6 V, V <sub>AH</sub> = 3.5 V	
				SI3705142/SI3705143			SI3705192/SI3705193					
				-55°C	25°C	85°C	0°C	25°C	70°C			
1	SWITCH	r <sub>DS(on)</sub>	Drain-Source ON Resistance	150	150	225	150	150	200	Ω	V <sub>D</sub> = 5 V	I <sub>S</sub> = -1 mA
2				200	200	300	200	200	300		V <sub>D</sub> = 0	
3				400	400	400	400	400	400		V <sub>D</sub> = -5 V    -142 and -192 only	
4	CH	I <sub>S(off)</sub>	Source OFF Leakage Current		-1	-100		-3	-150	nA	V <sub>S</sub> = -5 V, V <sub>D</sub> = 5 V	V <sub>En</sub> = 0.6 V
5				I <sub>D(off)</sub>	Drain OFF Leakage Current		-8	-500			-10	
6	IN	I <sub>INL</sub>	Input Current, Input Voltage Low		-1			-1		μA	V <sub>AL</sub> = 0	
7	DELAY	t <sub>transition</sub>	Switching Time Of Multiplexer		2.0			2.0		μs	See Switching Time Test circuit V <sub>S1</sub> = ±1 V, V <sub>S8</sub> = ±1 V, V <sub>S2-7</sub> = gnd	
8		t <sub>on</sub>	Turn-ON Time		1.2 Typ*			1.2 Typ*			See Switching Time Test Circuit V <sub>S(all)</sub> = 1 V	
9		t <sub>off</sub>	Turn-OFF Time		0.8 Typ*			0.8 Typ*				
10	NANC	t <sub>open</sub>	Break-Before-Make Interval		0.05 Typ*			0.05 Typ*				
11		C <sub>S(off)</sub>	Source OFF Capacitance		10 Typ*			10 Typ*		pF	V <sub>S</sub> = V <sub>D</sub> = 5 V	V <sub>En</sub> = 0.6 V f = 1 MHz
12	C <sub>D(off)</sub>	Drain OFF Capacitance		20 Typ*			20 Typ*					
13	P <sub>D</sub>	P <sub>D</sub>	Power Dissipation		175			175		mW	V <sub>-</sub> = -31 V, V <sub>+</sub> = 0	

\*Typical values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

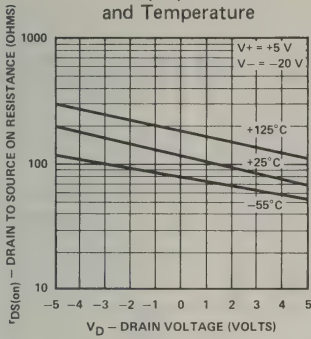
IPAA

## SWITCHING TIME TEST CIRCUIT

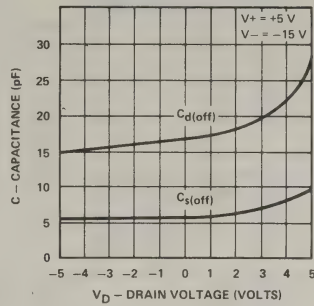
Switch output waveform shown for  $V_S =$  constant with logic input waveform as shown. Note that  $V_S$  may be + or - as per switching time test circuit.  $V_O$  is the steady state output with switch on. Feedthrough via gate capacitance may result in spikes at leading and trailing edge of output waveform.



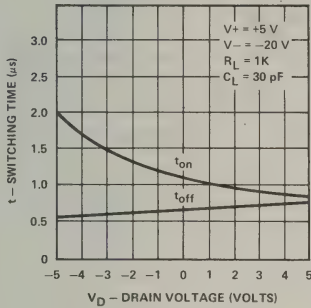
$r_{DS(on)}$  vs  $V_D$   
and Temperature



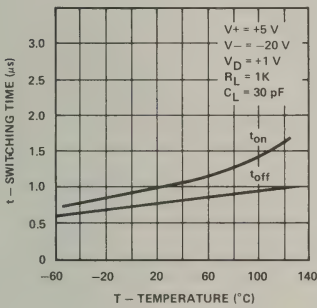
$C_D(off)$ ,  $C_S(off)$  vs  $V_D$



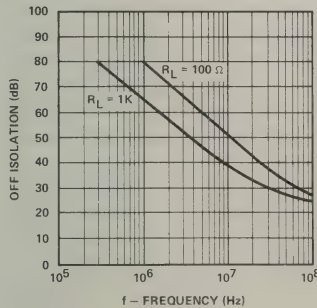
Switching Time vs  $V_D$



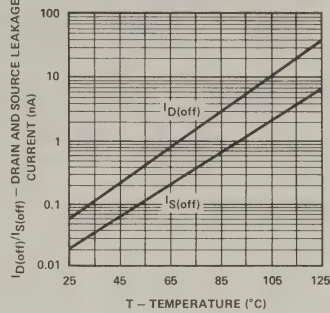
Switching Time vs  
Temperature



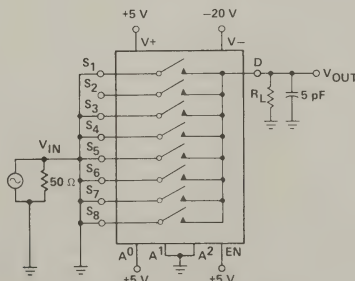
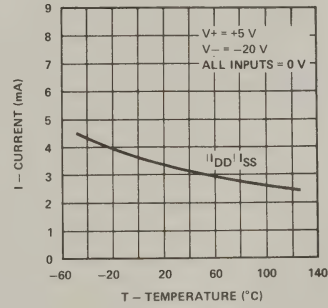
"OFF" Isolation vs  $R_L$   
and Frequency



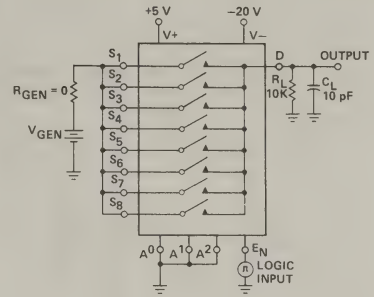
$I_D(off)/I_S(off)$  vs  
Temperature



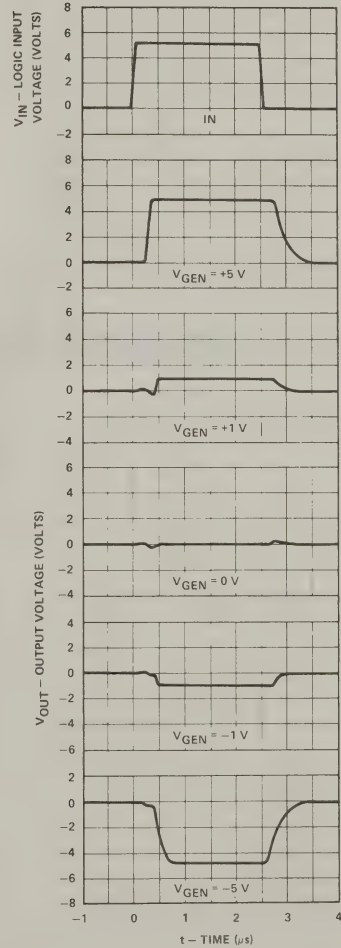
Supply Current vs  
Temperature



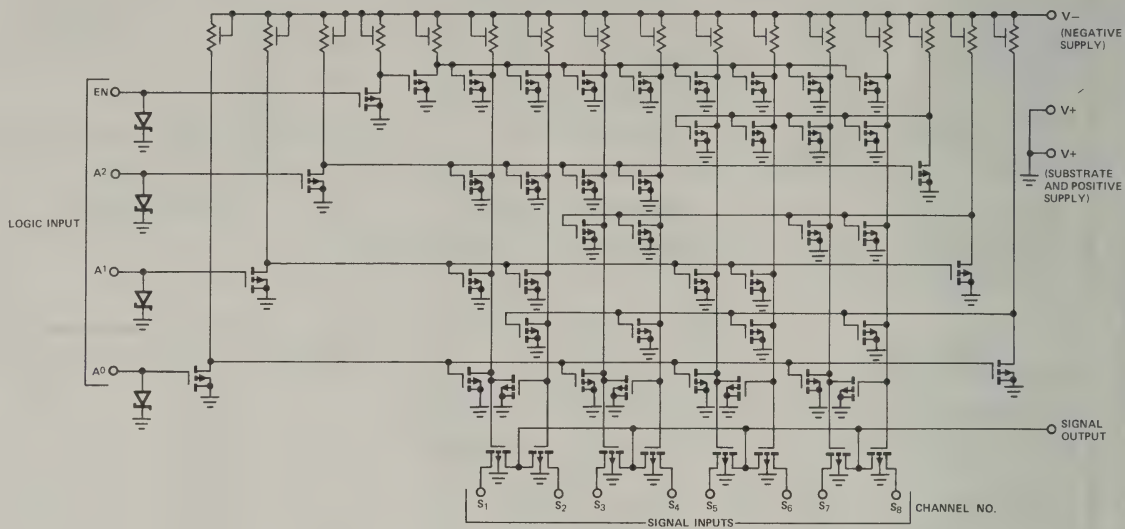
$$\text{"OFF" ISOLATION} = 20 \log \frac{|V_{OUT}|}{|V_{IN}|}$$



If  $R_{GEN}$ ,  $R_L$  or  $C_L$  is increased, there will be proportional increases in rise and/or fall RC times.



## SCHEMATIC DIAGRAM







Introduction	0
Interface	1
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Analog Multiplexers	4
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D/A Converters	8
Die Process & Topography	9
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# Index

## MULTI-CHANNEL FETs

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G122 .....	5-11
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*Stresses listed under "Absolute Maximum Ratings" may be applied (one at a time) to devices without resulting in permanent damage. This is a stress rating only and not subject to production testing. Exposure to absolute maximum rating conditions for extended periods may effect device reliability.*

# Monolithic 6-Channel Enhancement-Type MOS FET Switch



G115

*designed for . . .*

- Switching Analog Signals
- Multiplexing

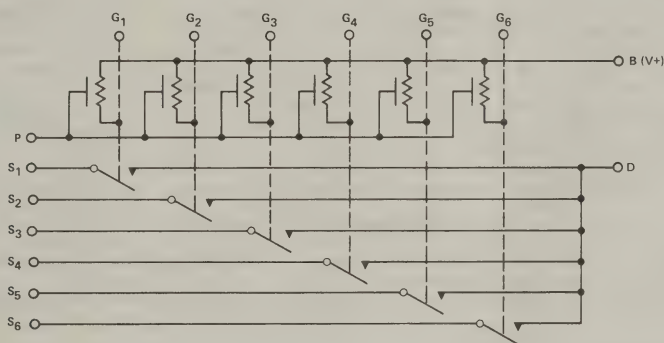
## BENEFITS

- Reduces External Component Requirements
  - Internal Zener Diode Protects the Gate
  - Six Switches Per Chip
  - Integrated MOS FET for Each Gate to Provide "Pull-Up" Current for Gate-Driver Circuit

## DESCRIPTION

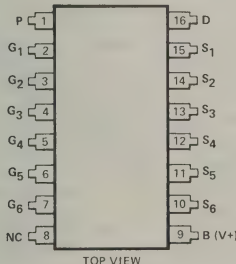
The G115 contains six enhancement-mode P-channel MOS FETs designed to function as analog switches. In the ON state each switch will conduct current equally well in either direction, and in the OFF state each switch will block voltages up to 30 V peak-to-peak. The switches are integrated on a silicon substrate (body). The switches have a common drain terminal (D) which will function equally well as a common source. In the same manner, the source terminals (S) will function equally well as drains. Each gate (G) is provided with a normally OFF "pull-up" MOS FET which may be turned ON to provide a current source to the gate-driving circuit. The pull-ups are turned ON or OFF by connecting the "P" terminal to a negative supply or to the "B" terminal respectively.

## FUNCTIONAL DIAGRAM



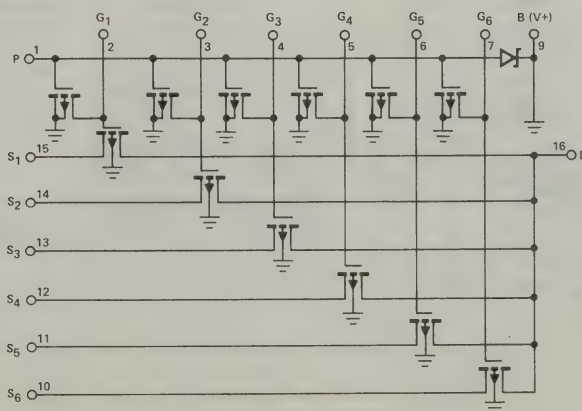
## PIN CONFIGURATION

Dual-In-Line Package



ORDER NUMBERS: G115AP OR G115BP  
SEE PACKAGE 12

## SCHEMATIC DIAGRAM



5

Multi-Channel FETs

## ABSOLUTE MAXIMUM RATINGS

$V_B$ to $V_S$ .....	-2 to 30 V
$V_B$ to $V_D$ .....	-2 to 30 V
$V_D$ to $V_S$ .....	$\pm 30$ V
$V_B$ to $V_G$ , $V_B$ to $V_P$ .....	35 V
$I_S$ , $I_D$ .....	100 mA
$I_G$ .....	5 mA
$I_P$ .....	100 $\mu$ A

Storage Temperature .....	-65 to 150°C
Operating Temperature (A Suffix) .....	-55 to 125°C
(B Suffix) .....	-20 to 85°C
Power Dissipation* .....	900 mW

\* All leads soldered or welded to PC board. Derate 12 mW/°C above 75°C.

## ELECTRICAL CHARACTERISTICS

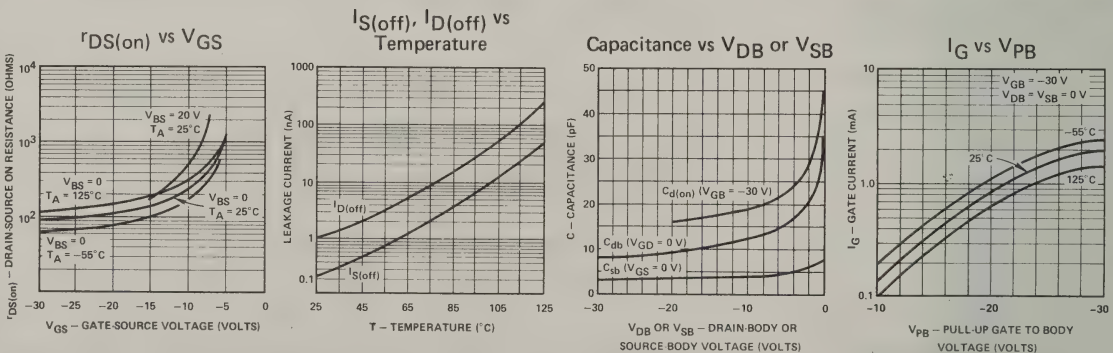
All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC		MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V <sub>DB</sub> = 0, V <sub>PB</sub> = 0		
		G115A			G115B						
		-55°C	25°C	125°C	-20°C	25°C	85°C				
1	r <sub>DS(on)</sub> Drain-Source ON Resistance	100	100	125	125	125	150	Ω	V <sub>DB</sub> = 0, V <sub>GD</sub> = -30 V	I <sub>S</sub> = -1 mA	
2		200	200	250	250	250	300		V <sub>DB</sub> = -10 V, V <sub>GD</sub> = -20 V		
3		450	450	600	500	500	600		V <sub>DB</sub> = -20 V, V <sub>GD</sub> = -10 V		
4	I <sub>S(off)</sub> Source OFF Leakage Current		-0.5	-500		-5	-500	nA	V <sub>SD</sub> = -20 V, V <sub>GD</sub> = 0		
5	I <sub>D(off)</sub> Drain OFF Leakage Current		-2.5	-2500		-10	-1000		V <sub>DS</sub> = -20 V, V <sub>GS</sub> = 0, V <sub>SB</sub> = 0		
6	I <sub>G(on)</sub> Gate ON Current		-0.8 to -2.4			-0.8 to -2.4		mA	V <sub>GB</sub> = -30 V, V <sub>PB</sub> = -30 V		
7	I <sub>GSS</sub> Gate-Channel Leakage Current		-0.5	-500		-5	-500	nA	V <sub>GB</sub> = -20 V		
8	V <sub>GS(th)</sub> Gate-Source Threshold Voltage	-1.5 to -4.0	-1.5 to -4.0	-1.5 to -4.0	-1.5 to -4.0	-1.5 to -4.0	-1.5 to -4.0	V	I <sub>D</sub> = -10 μA, V <sub>DG</sub> = 0, V <sub>SB</sub> = 0		
9	BV <sub>DSS</sub> Min Drain-Source Breakdown Voltage	-30	-30	-30	-30	-30	-30		I <sub>D</sub> = -50 μA, V <sub>GS</sub> = 0, V <sub>SB</sub> = 0		
10	BV <sub>SDS</sub> Min Source-Drain Breakdown Voltage	-30	-30	-30	-30	-30	-30		I <sub>S</sub> = -10 μA, V <sub>GD</sub> = 0		
11	BV <sub>GBS</sub> Min Gate-Body Breakdown Voltage	-35 to -90	-35 to -90	-35 to -90	-35 to -90	-35 to -90	-35 to -90		I <sub>G</sub> = -10 μA		
12	BV <sub>PBS</sub> Min Pull-Up Gate-Body Breakdown Voltage	-35 to -90	-35 to -90	-35 to -90	-35 to -90	-35 to -90	-35 to -90		I <sub>P</sub> = -10 μA, V <sub>GB</sub> = 0		
13	C <sub>gs</sub> Gate-Source Capacitance		0.9 Typ *			0.9 Typ *		pF	V <sub>DB</sub> = V <sub>SB</sub> = 0, Body Guarded	Drain Guarded	V <sub>GB</sub> = 0 f = 1 MHz
14	C <sub>gd</sub> Gate-Drain Capacitance		0.9 Typ *			0.9 Typ *			Source Guarded		
15	C <sub>ds(off)</sub> Drain-Source OFF Capacitance		0.4 Typ *			0.4 Typ *			Gate Guarded		
16	C <sub>sb</sub> Source-Body Capacitance		2 Typ *			2 Typ *			V <sub>DB</sub> = 0, V <sub>SB</sub> = -5 V	Gate and Drain Guarded	
17	C <sub>db</sub> Drain-Body Capacitance		12 Typ *			12 Typ *			V <sub>SB</sub> = 0, V <sub>DB</sub> = -5 V	Gate and Source Guarded	

\*Typical values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

MAB-A

## TYPICAL CHARACTERISTICS





# Monolithic 5-Channel Enhancement-Type MOS FET Switch

*designed for . . .*

- **Switching Analog Signals**
- **Multiplexing**

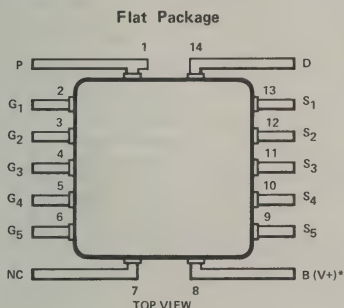
## BENEFITS

- **Reduces External Component Requirements**
  - Internal Zener Diode Protects the Gate
  - Five Switches Per Chip
  - Integrated MOS FET for Each Gate to Provide "Pull-Up" Current for Gate-Driver Circuit

## DESCRIPTION

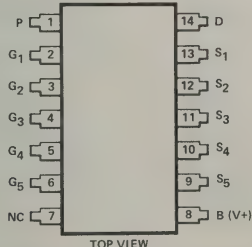
The G116 contains five enhancement-mode P-channel MOS FETs designed to function as analog switches. In the ON state each switch will conduct current equally well in either direction, and in the OFF state each switch will block voltages up to 30 V peak-to-peak. The switches are integrated on a silicon substrate (body). The switches have a common drain terminal (D) which will function equally well as a common source. In the same manner, the source terminals (S) will function equally well as drains. Each gate (G) is provided with a normally OFF "pull-up" MOS FET which may be turned ON to provide a current source to the gate-driving circuit. The pull-ups are turned ON or OFF by connecting the "P" terminal to a negative supply or to the "B" terminal respectively. It is recommended that the G116 be used for new designs.

## PIN CONFIGURATIONS

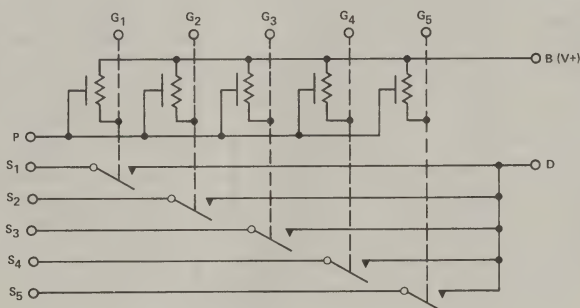


\* Common to Substrate and Base of Package

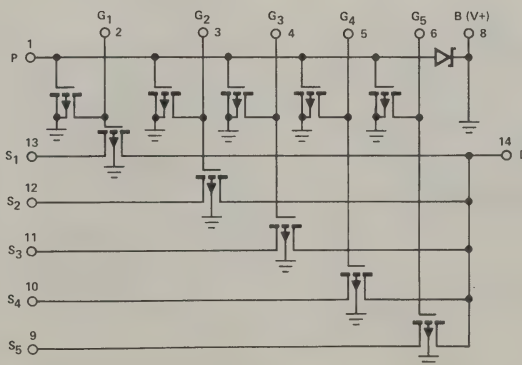
### Dual-In-Line Package



## FUNCTIONAL DIAGRAM



## SCHEMATIC DIAGRAM



## ABSOLUTE MAXIMUM RATINGS

$V_B$ to $V_S$ .....	-2 to 30 V
$V_B$ to $V_D$ .....	-2 to 30 V
$V_D$ to $V_S$ .....	$\pm 30$ V
$V_B$ to $V_G$ , $V_B$ to $V_P$ .....	35 V
$I_S$ , $I_D$ .....	100 mA
$I_G$ .....	5 mA
$I_P$ .....	100 $\mu$ A
Storage Temperature .....	-65 to 150°C

Operating Temperature ..... -55 to 125°C

Power Dissipation\*

Flat Package\*\* ..... 750 mW

14 Pin DIP\*\*\* ..... 825 mW

\*All leads soldered or welded to PC board.

\*\*Derate 10 mW/°C above 75°C.

\*\*\*Derate 11 mW/°C above 75°C.

## ELECTRICAL CHARACTERISTICS

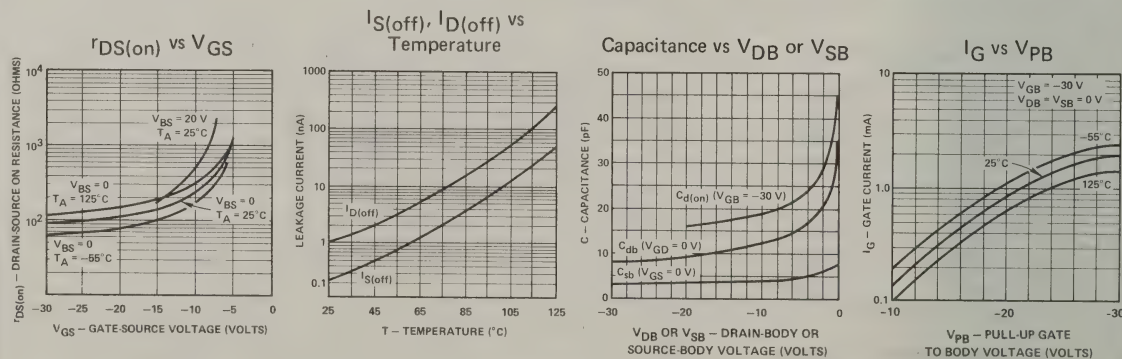
All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC		MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V <sub>DB</sub> = 0, V <sub>PB</sub> = 0			
		G116A			G116B							
		-55 °C	25 °C	125 °C	-20 °C	25 °C	85 °C					
1	r <sub>DS(on)</sub> Drain-Source ON Resistance	100	100	125	125	125	150	Ω	V <sub>DB</sub> = 0, V <sub>GD</sub> = -30 V		I <sub>S</sub> = -1 mA	
2		200	200	250	250	250	300		V <sub>DB</sub> = -10 V, V <sub>GD</sub> = -20 V			
3		450	450	600	500	500	600		V <sub>DB</sub> = -20 V, V <sub>GD</sub> = -10 V			
4	I <sub>S(off)</sub> Source OFF Leakage Current		-0.5	-500		-5	-500	nA	V <sub>SD</sub> = -20 V, V <sub>GD</sub> = 0			
5	I <sub>D(off)</sub> Drain OFF Leakage Current		-2.5	-2500		-10	-1000		V <sub>DS</sub> = -20 V, V <sub>GS</sub> = 0, V <sub>SB</sub> = 0			
6	I <sub>G(on)</sub> Gate ON Current		-0.8 to -2.4			-0.8 to -2.4		mA	V <sub>GB</sub> = -30 V, V <sub>PB</sub> = -30 V			
7	I <sub>GSS</sub> Gate-Channel Leakage Current		-0.5	-500		-5	-500	nA	V <sub>GB</sub> = -20 V			
8	V <sub>GS(th)</sub> Gate-Source Threshold Voltage	-1.5 to -4.0	-1.5 to -4.0	-1.5 to -4.0	-1.4 to -4.0	-1.5 to -4.0	-1.5 to -4.0	V	I <sub>D</sub> = -10 μA, V <sub>SB</sub> = 0, V <sub>DG</sub> = 0			
9	BV <sub>DSS</sub> Min Drain-Source Breakdown Voltage	-30	-30	-30	-30	-30	-30		I <sub>D</sub> = -50 μA, V <sub>GS</sub> = 0, V <sub>SB</sub> = 0			
10	BV <sub>SDS</sub> Min Source-Drain Breakdown Voltage	-30	-30	-30	-30	-30	-30		I <sub>S</sub> = -10 μA, V <sub>GD</sub> = 0			
11	BV <sub>GBS</sub> Min Gate-Body Breakdown Voltage	-35 to -90	-35 to -90	-35 to -90	-35 to -90	-35 to -90	-35 to -90		I <sub>G</sub> = -10 μA			
12	BV <sub>PBS</sub> Min Pull-Up Gate-Body Breakdown Voltage	-35 to -90	-35 to -90	-35 to -90	-35 to -90	-35 to -90	-35 to -90		I <sub>P</sub> = -10 μA, V <sub>GB</sub> = 0			
13	C <sub>gs</sub> Gate-Source Capacitance		0.9 Typ *			0.9 Typ *		pF	V <sub>DB</sub> = V <sub>SB</sub> = 0, Body Guarded	Drain Guarded	V <sub>GB</sub> = 0 f = 1 MHz	
14	C <sub>gd</sub> Gate-Drain Capacitance		0.9 Typ *			0.9 Typ *				Source Guarded		
15	C <sub>ds(off)</sub> Drain-Source OFF Capacitance		0.4 Typ *			0.4 Typ *				Gate Guarded		
16	C <sub>sb</sub> Source-Body Capacitance		6 Typ *			6 Typ *				V <sub>DB</sub> = 0, V <sub>SB</sub> = -5 V		Gate and Drain Guarded
17	C <sub>db</sub> Drain-Body Capacitance		12 Typ *			12 Typ *				V <sub>SB</sub> = 0, V <sub>DB</sub> = -5 V		Gate and Source Guarded

\*Typical values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

MAB-A

## TYPICAL CHARACTERISTICS



# Monolithic 5-Channel Enhancement-Type MOS FET Switch

*designed for . . .*

- Switching Analog Signals
- Multiplexing with Enable Switch

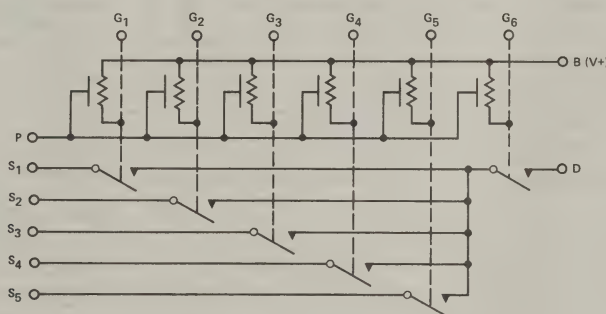
## BENEFITS

- Reduces External Component Requirements
  - Internal Zener Diode Protects the Gate
  - Five Switches Per Chip
  - Integrated MOS FET for Each Gate to Provide "Pull-Up" Current for Gate-Driver Circuit

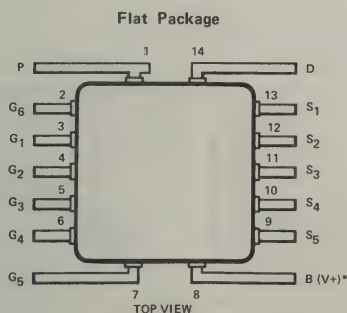
## DESCRIPTION

The G117 contains six enhancement-mode P-channel MOS FETs designed to function as analog switches. In the ON state each switch will conduct current equally well in either direction, and in the OFF state each switch will block voltages up to 20 V peak-to-peak. The switches are integrated on a silicon substrate (body). The drains of five of the switches are internally connected to the source of the sixth switch. This arrangement is intended for use of the device as a 5-channel first-level and one-channel second-level multiplexer. Each of the six gates are provided with an internal "pull-up" current which may be turned ON or OFF by connecting the pull-up control terminal (P) to a negative supply or to the body (B) terminal.

## FUNCTIONAL DIAGRAM



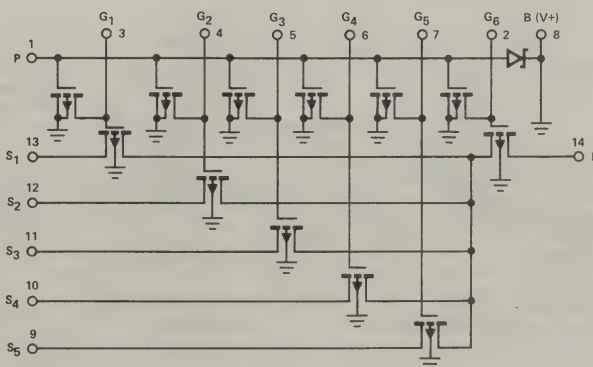
## PIN CONFIGURATION



ORDER NUMBER: G117AL  
SEE PACKAGE 5

\*Common to Substrate and Base of Package

## SCHEMATIC DIAGRAM



5

Multi-Channel FETs



## ABSOLUTE MAXIMUM RATINGS

$V_B$ to $V_S$ .....	-2 to 30 V
$V_B$ to $V_D$ .....	-2 to 30 V
$V_D$ to $V_S$ .....	$\pm 30$ V
$V_B$ to $V_G$ , $V_B$ to $V_P$ .....	35 V
$I_S$ , $I_D$ .....	100 mA
$I_G$ .....	5 mA
$I_P$ .....	100 $\mu$ A

Storage Temperature .....	-65 to 150°C
Operating Temperature (A Suffix) .....	-55 to 125°C
(B Suffix) .....	-20 to 85°C

Power Dissipation\* .....

\*All leads soldered or welded to PC board. Derate 10 mW/°C above 75°C.

## ELECTRICAL CHARACTERISTICS

All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

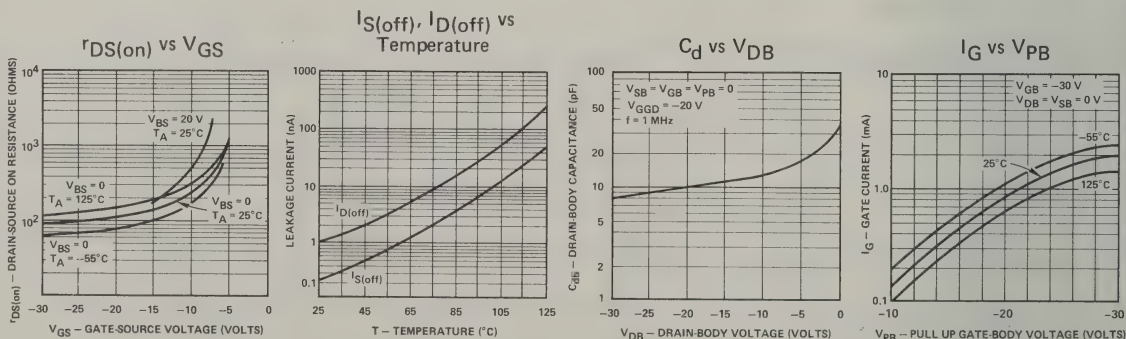
CHARACTERISTIC		MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V <sub>DB</sub> = 0, V <sub>PB</sub> = 0		
		G117A			G117B						
		-55° C	25° C	125° C	-20° C	25° C	85° C				
1	r <sub>DS(on)</sub> * Drain-Source ON Capacitance	100	100	125	125	125	150	Ω	V <sub>DB</sub> = 0, V <sub>GD</sub> = -30 V		
2		200	200	250	250	250	300		V <sub>DB</sub> = -10 V, V <sub>GD</sub> = -20 V		
3		450	450	600	500	500	600		V <sub>DB</sub> = -20 V, V <sub>GD</sub> = -10 V		
4		I <sub>S(off)</sub> Source OFF Leakage Current		-0.5	-500	-5	-10		V <sub>SD</sub> = -20 V, V <sub>GD</sub> = 0		
5	I <sub>D(off)</sub> Drain OFF Leakage Current	-2.5	-2500		-10	-500	nA	V <sub>DS</sub> = -20 V, V <sub>GS</sub> = 0, V <sub>G6S</sub> = -30 V, V <sub>SB</sub> = 0			
6	I <sub>D(off)</sub> Drain OFF Leakage Current	-0.5	-500		-5	-100		V <sub>DS</sub> = -20 V, V <sub>GS</sub> = -30 V, V <sub>G6B</sub> = 0, V <sub>SB</sub> = 0			
7	I <sub>G(on)</sub> Gate ON Current	-0.8 to -2.4			-0.8 to -2.4		mA	V <sub>GB</sub> = -30 V, V <sub>DB</sub> = -30 V			
8	I <sub>GSS</sub> Gate-Channel Leakage Current	-0.5	-500		-5	-500	nA	V <sub>GB</sub> = -20 V			
9	V <sub>GS(th)</sub> Gate-Source Threshold Voltage	-1.5 to -4.0	-1.5 to -4.0	-1.5 to -4.0	-1.5 to -4.0	-1.5 to -4.0	-1.5 to -4.0	V	I <sub>S</sub> = 10 μA, V <sub>DG1-5</sub> = 0, V <sub>GB6</sub> = -20 V		
10	V <sub>GS(th)</sub> Gate-Source Threshold Voltage	-1.5 to -4.0	-1.5 to -4.0	-1.5 to -4.0	-1.5 to -4.0	-1.5 to -4.0	-1.5 to -4.0		I <sub>S1</sub> = 10 μA, V <sub>DG6</sub> = 0, V <sub>GB1</sub> = -20 V		
11	BV <sub>DSS</sub> Min Drain-Source Breakdown Voltage	-30	-30	-30	-30	-30	-30		I <sub>D</sub> = -50 μA, V <sub>GS</sub> = 0, V <sub>SB</sub> = 0		
12	BV <sub>SDS</sub> Min Source-Drain Breakdown Voltage	-30	-30	-30	-30	-30	-30		I <sub>S</sub> = -10 μA, V <sub>GD</sub> = 0		
13	BV <sub>GBS</sub> Min Gate-Body Breakdown Voltage	-35 to -90	-35 to -90	-35 to -90	-35 to -90	-35 to -90	-35 to -90		I <sub>G</sub> = -10 μA		
14	BV <sub>PBS</sub> Min Pull-Up Gate-Body Breakdown Voltage	-35 to -90	-35 to -90	-35 to -90	-35 to -90	-35 to -90	-35 to -90		I <sub>P</sub> = -10 μA, V <sub>GB</sub> = 0		
15	C <sub>gs</sub> Gate-Source Capacitance	0.9 Typ**			0.9 Typ**			pF	V <sub>DB</sub> = V <sub>SB</sub> = 0, Body Guarded	Drain Guarded	V <sub>GB</sub> = 0 f = 1 MHz
16	C <sub>gd</sub> Gate-Drain Capacitance	0.9 Typ**			0.9 Typ**					Source Guarded	
17	C <sub>ds(off)</sub> * Drain-Source OFF Capacitance	0.4 Typ**			0.4 Typ**					Gate Guarded	
18	C <sub>sb</sub> Source-Body Capacitance	2 Typ**			2 Typ**				V <sub>DB</sub> = 0, V <sub>SB</sub> = -5 V Gate and Drain Guarded		
19	C <sub>db</sub> Drain-Body Capacitance	12 Typ**			12 Typ**				V <sub>S(1-5)B</sub> = 0, V <sub>G(1-5)B</sub> = 0, V <sub>G6B</sub> = -30 V, V <sub>DB</sub> = -5 V, All Gates and Sources Guarded		

\*This is resistance (capacitance) from each source to common internal node. Multiply resistance by two for total resistance from inputs to output.

MAB

\*\*Typical values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

## TYPICAL CHARACTERISTICS





# Monolithic 6-Channel Enhancement-Type MOS FET Switch

*designed for . . .*

- Switching Analog Signals
- Multiplexing

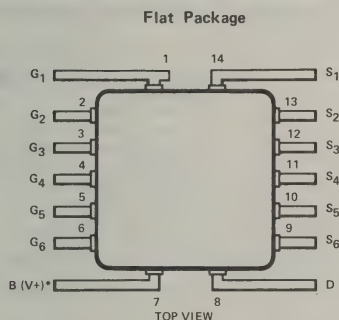
## BENEFITS

- Reduces External Component Requirements
  - Internal Zener Diode Protects the Gate
  - Six Switches Per Chip

## DESCRIPTION

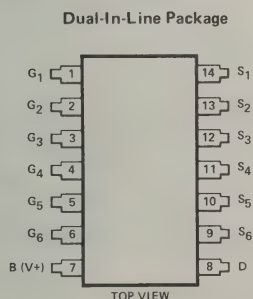
The G118 contains six enhancement-mode P-channel MOS FETs designed to function as analog switches. In the ON state each switch will conduct current equally well in either direction, and in the OFF state each switch will block voltages up to 20 V peak-to-peak. The switches are integrated on a common substrate (body). They have a common drain terminal (D) which will function equally well as a common source; likewise, the source terminals will function as drains.

## PIN CONFIGURATIONS



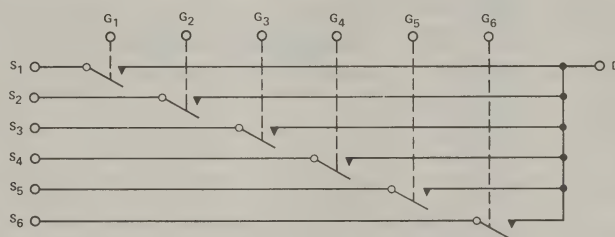
ORDER NUMBER: G118AL  
SEE PACKAGE 5

\*Common to Substrate and Base of Package

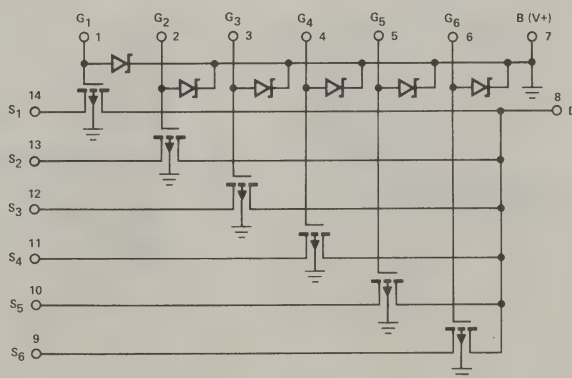


ORDER NUMBER: G118AP  
SEE PACKAGE 11

## FUNCTIONAL DIAGRAM



## SCHEMATIC DIAGRAM



**Multi-Channel FETs**

**5**

## ABSOLUTE MAXIMUM RATINGS

$V_B$ to $V_S$ .....	-2 to 30 V
$V_B$ to $V_D$ .....	-2 to 30 V
$V_D$ to $V_S$ .....	$\pm 30$ V
$V_B$ to $V_G$ .....	35 V
$I_S, I_D$ .....	100 mA
$I_G$ .....	5 mA
Storage Temperature .....	-65 to 150°C

Operating Temperature (A Suffix) ..... -55 to 125°C  
(B Suffix) ..... -20 to 85°C

## Power Dissipation\*

Flat Package\*\* ..... 750 mW  
14 Pin DIP\*\*\* ..... 825 mW

\* All leads soldered or welded to PC board.

\*\* Derate 10 mW/°C above 75°C.

\*\*\* Derate 11 mW/°C above 75°C.

## ELECTRICAL CHARACTERISTICS

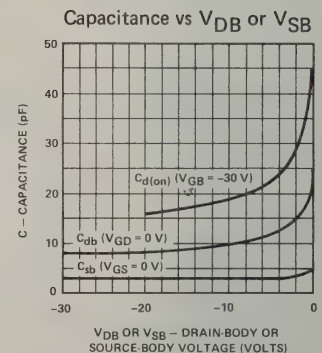
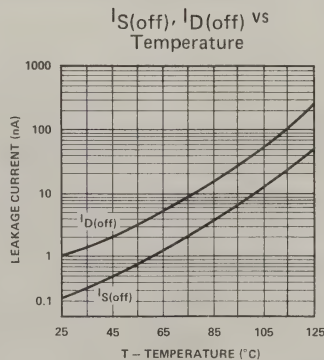
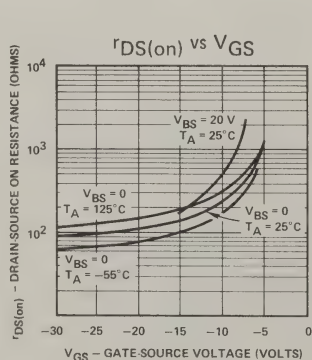
All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC		MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V <sub>DB</sub> = 0			
		G118A			G118B							
		-55°C	25°C	125°C	-20°C	25°C	85°C					
1	T <sub>DS(on)</sub>	Drain-Source ON Resistance	100	100	125	125	125	150	Ω	V <sub>DB</sub> = 0, V <sub>GD</sub> = -30 V		I <sub>S</sub> = -1 mA
2		200	200	250	250	250	300	V <sub>DB</sub> = -10 V, V <sub>GD</sub> = -20 V				
3		450	450	600	500	500	600	V <sub>DB</sub> = -20 V, V <sub>GD</sub> = -10 V				
4	I <sub>S(off)</sub>	Source OFF Leakage Current	-0.5	-500		-5	-500	nA	V <sub>SD</sub> = -20 V, V <sub>GD</sub> = 0			
5	I <sub>D(off)</sub>	Drain OFF Leakage Current	-3	-3000		-10	-1000		V <sub>DS</sub> = -20 V, V <sub>GS</sub> = 0, V <sub>SB</sub> = 0			
6	I <sub>GSS</sub>	Gate-Channel Leakage Current	-0.5	-500		-5	-500		V <sub>GB</sub> = -20 V			
7	V <sub>GS(th)</sub>	Gate-Source Threshold Voltage	-1.5 to -4.0	-1.5 to -4.0	-1.5 to -4.0	-1.5 to -4.0	-1.5 to -4.0	V	I <sub>D</sub> = -10 μA, V <sub>GD</sub> = 0, V <sub>SB</sub> = 0			
8	BV <sub>DSS</sub> Min	Drain-Source Breakdown Voltage	-30	-30	-30	-30	-30		I <sub>D</sub> = -50 μA, V <sub>GS</sub> = 0, V <sub>SB</sub> = 0			
9	BV <sub>SDS</sub> Min	Source-Drain Breakdown Voltage	-30	-30	-30	-30	-30		I <sub>S</sub> = -10 μA, V <sub>GD</sub> = 0			
10	BV <sub>GSS</sub> Min	Gate-Body Breakdown Voltage	-35 to -90	-35 to -90	-35 to -90	-35 to -90	-35 to -90		I <sub>G</sub> = -10 μA			
11	C <sub>gs</sub>	Gate-Source Capacitance		0.9 Typ *			0.9 Typ *	pF	V <sub>DB</sub> = V <sub>SB</sub> = 0, Body Guarded	Drain Guarded	V <sub>GB</sub> = 0 f = 1 MHz	
12	C <sub>gd</sub>	Gate-Drain Capacitance		0.9 Typ *			0.9 Typ *			Source Guarded		
13	C <sub>ds(off)</sub>	Drain-Source OFF Capacitance		0.4 Typ *			0.4 Typ *			Gate Guarded		
14	C <sub>sb</sub>	Source-Body Capacitance		2 Typ *			2 Typ *		V <sub>DB</sub> = 0, V <sub>SB</sub> = -5 V	Gate and Drain Guarded		
15	C <sub>db</sub>	Drain-Body Capacitance		12 Typ *			12 Typ *		V <sub>SB</sub> = 0, V <sub>DB</sub> = -5 V	Gate and Source Guarded		

\* Typical values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

MABA

## TYPICAL CHARACTERISTICS



# Monolithic 6-Channel Enhancement-Type MOS FET Switch

*designed for . . .*

- Switching Analog Signals such as Differential Inputs
- Multiplexing

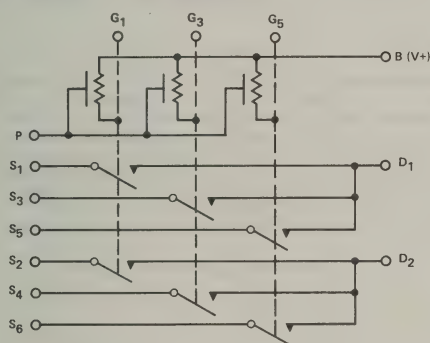
## BENEFITS

- Reduces External Component Requirements
  - Internal Zener Diode Protects the Gate
  - Six Switches Per Chip
  - Integrated MOS FET for Each Gate to Provide "Pull-Up" Current for Gate-Driver Circuit

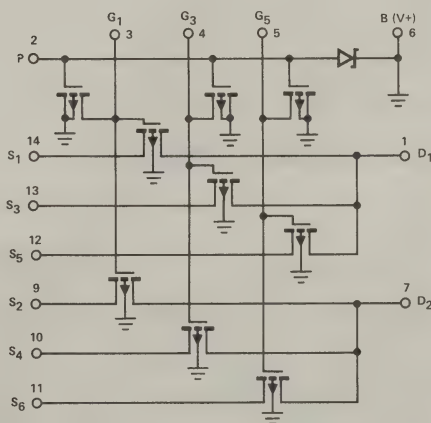
## DESCRIPTION

The G119 contains six enhancement-mode P-channel MOS FETs designed to function as analog switches. In the ON state each switch will conduct current equally well in either direction, and in the OFF state each switch will block voltages up to 30 V peak-to-peak. The switches are integrated onto a silicon substrate (body) and are internally connected into two groups of three switches per group. This arrangement facilitates the switching or multiplexing of differential analog signals. Each group has a common drain terminal (D<sub>1</sub> and D<sub>2</sub>) which will function equally well as a common source. Each gate terminal (G) controls a pair of switches and is provided with a normally-OFF "pull-up" MOS FET which may be turned ON to provide a current source to the gate-driving circuit. The pull-ups are turned ON or OFF by connecting the "P" terminal to a negative supply or to the "B" terminal respectively.

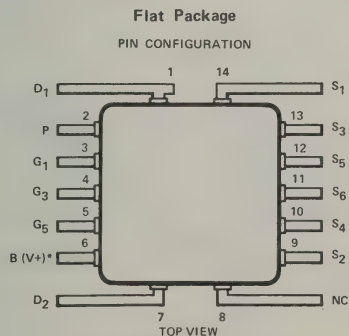
## FUNCTIONAL DIAGRAM



## SCHEMATIC DIAGRAM



## PIN CONFIGURATION



ORDER NUMBER: G119AL  
SEE PACKAGE 5

\*Common to Substrate and Base of Package



## ABSOLUTE MAXIMUM RATINGS

$V_B$ to $V_S$ .....	-2 to 30 V
$V_B$ to $V_D$ .....	-2 to 30 V
$V_D$ to $V_S$ .....	$\pm 30$ V
$V_B$ to $V_G$ , $V_B$ to $V_P$ .....	35 V
$I_S$ , $I_D$ .....	100 mA
$I_G$ .....	5 mA

$I_P$ .....	100 $\mu$ A
Storage Temperature .....	-65 to 150°C
Operating Temperature (A Suffix) .....	-55 to 125°C
(B Suffix) .....	-20 to 85°C
Power Dissipation* .....	750 mW
*All leads soldered or welded to PC board. Derate 10 mW/°C above 75°C.	

## ELECTRICAL CHARACTERISTICS

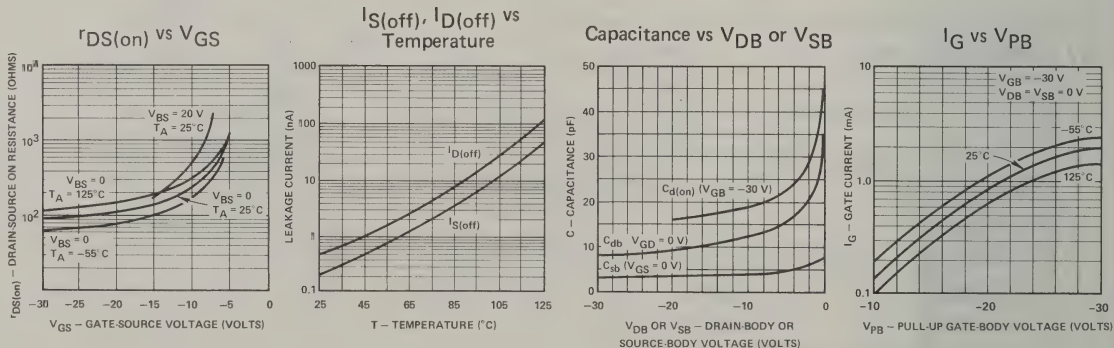
All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC			MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V <sub>DB</sub> = 0, V <sub>PB</sub> = 0				
			G119A			G119B								
			-55°C	25°C	125°C	-20°C	25°C	85°C						
1	DS(on)	Drain-Source ON Resistance	100	100	125	125	125	150	Ω	V <sub>DB</sub> = 0, V <sub>GD</sub> = -30 V				
2			200	200	250	250	250	300		V <sub>DB</sub> = -10 V, V <sub>GD</sub> = -20 V				
3			450	450	600	500	500	600		V <sub>DB</sub> = -20 V, V <sub>GD</sub> = -10 V				
4	STATIC	S(off)	Source OFF Leakage Current		-0.5	-500	-5	-500	nA	V <sub>SD</sub> = -20 V, V <sub>GD</sub> = 0				
5		D(off)	Drain OFF Leakage Current		-1.5	-1500	-10	-1000		V <sub>DS</sub> = -20 V, V <sub>GS</sub> = 0, V <sub>SB</sub> = 0				
6		I <sub>G(on)</sub>	Gate ON Current		-0.8 to -2.4		-0.8 to -2.4			mA	V <sub>GB</sub> = -30 V, V <sub>PB</sub> = -30 V			
7	I <sub>GSS</sub>	Gate-Channel Leakage Current		-0.5	-500	-5	-500	nA	V <sub>GB</sub> = -20 V					
8	V <sub>GS(th)</sub>	Gate-Source Threshold Voltage	-1.5 to -4.0	-1.5 to -4.0	-1.5 to -4.0	-1.5 to -4.0	-1.5 to -4.0	-1.5 to -4.0	V	I <sub>D</sub> = -10 μA, V <sub>SB</sub> = 0, V <sub>GD</sub> = 0				
9	BV <sub>DSS</sub> Min	Drain-Source Breakdown Voltage	-30	-30	-30	-30	-30	-30		I <sub>D</sub> = -50 μA, V <sub>GS</sub> = 0, V <sub>SB</sub> = 0				
10	BV <sub>SDS</sub> Min	Source-Drain Breakdown Voltage	-30	-30	-30	-30	-30	-30		I <sub>S</sub> = -10 μA, V <sub>GD</sub> = 0				
11	BV <sub>GBS</sub> Min	Gate-Body Breakdown Voltage	-35 to -90	-35 to -90	-35 to -90	-35 to -90	-35 to -90	-35 to -90		I <sub>G</sub> = -10 μA				
12	BV <sub>PBS</sub> Min	Pull-Up Gate-Body Breakdown Voltage	-35 to -90	-35 to -90	-35 to -90	-35 to -90	-35 to -90	-35 to -90		I <sub>P</sub> = -10 μA, V <sub>GB</sub> = 0				
13	DYNAMIC	C <sub>gs</sub>	Gate-Source Capacitance		1.8 Typ *		1.8 Typ *		pF	V <sub>DB</sub> = V <sub>SB</sub> = 0, Body Guarded	Drain Guarded		V <sub>GB</sub> = 0 f = 1 MHz	
14		C <sub>gd</sub>	Gate-Drain Capacitance		1.8 Typ *		1.8 Typ *				Source Guarded			
15		C <sub>ds(off)</sub>	Drain-Source OFF Capacitance		0.4 Typ *		0.4 Typ *				Gate Guarded			
16		C <sub>sb</sub>	Source-Body Capacitance		2 Typ *		2 Typ *			V <sub>DB</sub> = 0, V <sub>SB</sub> = -5 V		Gate and Drain Guarded		
17		C <sub>db</sub>	Drain-Body Capacitance		6 Typ *		6 Typ *			V <sub>SB</sub> = 0, V <sub>DB</sub> = -5 V		Gate and Source Guarded		

\*Typical values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

MABB

## TYPICAL CHARACTERISTICS





# Monolithic 4-Channel Enhancement-Type MOS FET Switch

*designed for . . .*

- Switching Analog Signals such as Differential Inputs
- Multiplexing

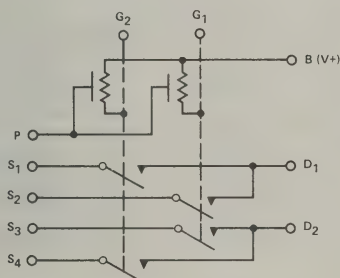
## BENEFITS

- Reduces External Component Requirements
  - Internal Zener Diode Protects the Gate
  - Four Switches Per Chip
  - Integrated MOS FET for Each Gate to Provide "Pull-Up" Current for Gate-Driver Circuit

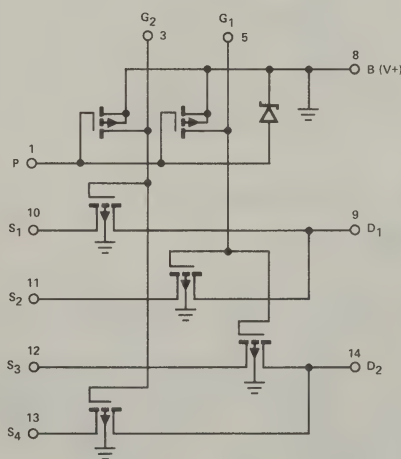
## DESCRIPTION

The G122 contains four enhancement-mode P-channel MOS FETs designed to function as analog switches. In the ON state each switch will conduct current equally well in either direction, and in the OFF state each switch will block voltages up to 30 V peak-to-peak. The switches are integrated onto a silicon substrate (body) and are internally connected into two groups of two switches per group. This arrangement facilitates the switching or multiplexing of differential analog signals. Each group has a common drain terminal ( $D_1$  and  $D_2$ ) which will function equally well as a common source. Each gate terminal ( $G$ ) controls a pair of switches and is provided with a normally-OFF "pull-up" MOS FET which may be turned ON to provide a current source to a gate-driving circuit. The pull-ups are turned ON or OFF by connecting the "P" terminal to a negative supply or to the "B" terminal respectively.

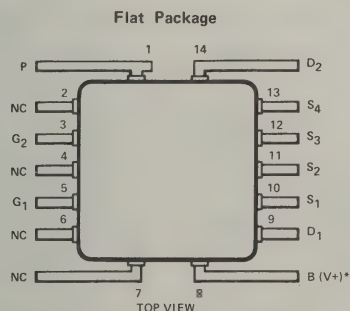
## FUNCTIONAL DIAGRAM



## SCHEMATIC DIAGRAM



## PIN CONFIGURATION



ORDER NUMBER: G122AL  
SEE PACKAGE 5

\*Common to Substrate and Base of Package

## ABSOLUTE MAXIMUM RATINGS

$V_B$ to $V_S$ .....	-2 to 30 V
$V_B$ to $V_D$ .....	-2 to 30 V
$V_D$ to $V_S$ .....	$\pm 30$ V
$V_B$ to $V_G$ or $V_P$ .....	35 V
$I_S$ , $I_D$ .....	100 mA
$I_G$ .....	5 mA
$I_P$ .....	100 $\mu$ A

Storage Temperature .....	-65 to 150°C
Operating Temperature (A Suffix) .....	-55 to 125°C
(B Suffix) .....	-20 to 85°C
Power Dissipation* .....	750 mW

\*All leads soldered or welded to PC board. Derate 10 mW/°C above 75°C.

## ELECTRICAL CHARACTERISTICS

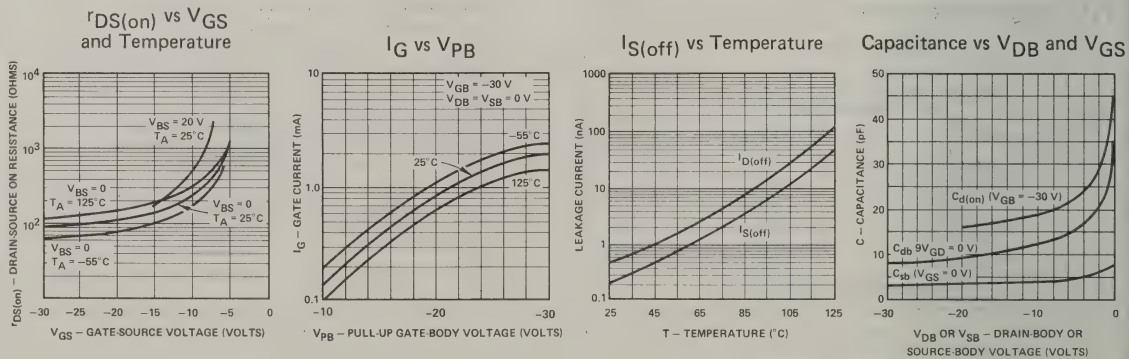
All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC		MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V <sub>DB</sub> = 0, V <sub>PB</sub> = 0		
		A SUFFIX			B SUFFIX						
		-55°C	25°C	125°C	-20°C	25°C	85°C				
1	r <sub>DS(on)</sub> Drain-Source ON Resistance	100	100	125	125	125	150	Ω	V <sub>DB</sub> = 0, V <sub>GD</sub> = -30 V		
2		200	200	250	250	250	300		V <sub>DB</sub> = -10 V, V <sub>GD</sub> = -20 V		
3		450	450	600	500	500	600		V <sub>DB</sub> = -20 V, V <sub>GD</sub> = -10 V		
4	I <sub>S(off)</sub> Source OFF Leakage Current		0.5	-500		-5	-500	nA	V <sub>SD</sub> = -20 V, V <sub>GD</sub> = 0		
5	I <sub>D(off)</sub> Drain OFF Leakage Current		-1	-1000		-10	-1000		V <sub>DS</sub> = -20 V, V <sub>GS</sub> = 0, V <sub>SB</sub> = 0		
6	I <sub>G(on)</sub> Gate ON Current		-0.8 to -2.4			-0.8 to -2.4		mA	V <sub>GB</sub> = -30 V, V <sub>PB</sub> = -30 V		
7	I <sub>GSS</sub> Gate-Channel Leakage Current		-0.5	-500		-5	-500	nA	V <sub>GB</sub> = -20 V		
8	V <sub>GS(th)</sub> Gate-Source Threshold Voltage	-1.5 to -4.0	-1.5 to -4.0	-1.5 to -4.0	-1.5 to -4.0	-1.5 to -4.0	-1.5 to -4.0	V	I <sub>D</sub> = -10 μA, V <sub>GD</sub> = 0, V <sub>SB</sub> = 0		
9	BV <sub>DSS</sub> Min Drain-Source Breakdown Voltage	-30	-30	-30	-30	-30	-30		I <sub>D</sub> = -10 μA, V <sub>GS</sub> = 0, V <sub>SB</sub> = 0		
10	BV <sub>SDS</sub> Min Source-Drain Breakdown Voltage	-30	-30	-30	-30	-30	-30		I <sub>S</sub> = -10 μA, V <sub>GD</sub> = 0		
11	BV <sub>GBS</sub> Min Gate-Body Breakdown Voltage	-35 to -90	-35 to -90	-35 to -90	-35 to -90	-35 to -90	-35 to -90		I <sub>S</sub> = -10 μA		
12	BV <sub>PBS</sub> Min Pull-Up Gate-Body Breakdown Voltage	-35 to -90	-35 to -90	-35 to -90	-35 to -90	-35 to -90	-35 to -90		I <sub>P</sub> = -10 μA, V <sub>GB</sub> = 0		
13	C <sub>gs</sub> Gate-Source Capacitance		1.8 Typ*			1.8 Typ*		pF	V <sub>DB</sub> = V <sub>SB</sub> = 0 Body Guarded	Drain Guarded	V <sub>GB</sub> = 0 f = 1 MHz
14	C <sub>gd</sub> Gate-Drain Capacitance		1.8 Typ*			1.8 Typ*			Source Guarded		
15	C <sub>ds(off)</sub> Drain-Source OFF Capacitance		0.4 Typ*			0.4 Typ*			Gate Guarded		
16	C <sub>sb</sub> Source-Body Capacitance		2 Typ*			2 Typ*			V <sub>DB</sub> = 0, V <sub>SB</sub> = -5 V	Gate and Drain Guarded	
17	C <sub>db</sub> Drain-Body Capacitance		6 Typ*			6 Typ*			V <sub>SB</sub> = 0, V <sub>DB</sub> = -5 V	Gate and Source Guarded	

\*Typical values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

MABB

## TYPICAL CHARACTERISTICS



# Monolithic 4-Channel Enhancement-Type MOS FET Switch



G123

*designed for . . .*

- Switching Analog Signals
- Multiplexing

## BENEFITS

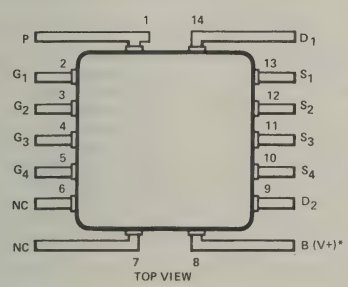
- Reduces External Component Requirements
  - Internal Zener Diode Protects the Gate
  - Four Switches Per Chip
  - Integrated MOS FET for Each Gate to Provide "Pull-Up" Current for Gate-Driver Circuit

## DESCRIPTION

The G123 contains four enhancement-mode P-channel MOS FETs designed to function as analog switches. In the ON state each switch will conduct current equally well in either direction, and in the OFF state each switch will block voltages up to 20 V peak-to-peak. The switches are integrated on a silicon substrate (body). Separate source and gate connections are provided for each switch; the drains are connected in pairs to two drain terminals. Functions of the drain and source terminals may be interchanged with comparable performance. Each gate terminal (G) is provided with a normally-OFF "pull-up" MOS FET which may be turned ON to provide a current source to a gate-driving circuit. The pull-ups are turned ON or OFF by connecting the "P" terminal to a negative supply or to the "B" terminal respectively.

## PIN CONFIGURATIONS

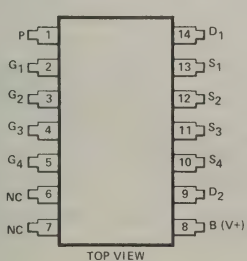
Flat Package



ORDER NUMBER: G123AL  
SEE PACKAGE 5

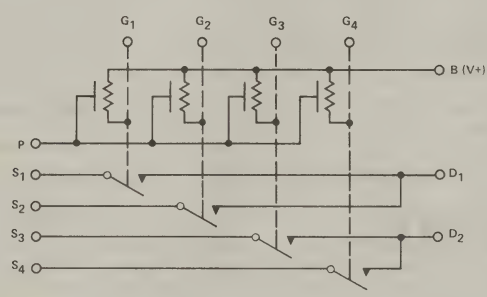
\*Common to Substrate and Base of Package

Dual-In-Line Package

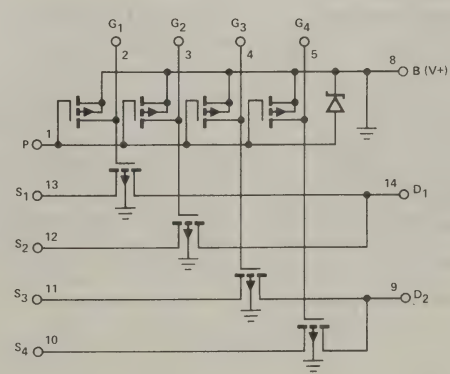


ORDER NUMBERS: G123AP OR G123BP  
SEE PACKAGE 11

## FUNCTIONAL DIAGRAM



## SCHEMATIC DIAGRAM



5  
Multi-Channel FETs



## ABSOLUTE MAXIMUM RATINGS

$V_B$ to $V_S$ .....	-2 to 35 V
$V_B$ to $V_D$ .....	-2 to 30 V
$V_D$ to $V_S$ .....	$\pm 30$ V
$V_B$ to $V_G$ or $V_P$ .....	35 V
$I_S$ , $I_D$ .....	100 mA
$I_G$ .....	5 mA
$I_P$ .....	100 $\mu$ A
Storage Temperature .....	-65 to 150°C

Operating Temperature (A Suffix) ..... -55 to 125°C  
(B Suffix) ..... -20 to 85°C

## Power Dissipation\*

Flat Package\*\* ..... 750 mW  
14 Pin DIP\*\*\* ..... 825 mW

\*All leads soldered or welded or PC board.

\*\*Derate 10 mW/°C above 75°C.

\*\*\*Derate 11 mW/°C above 75°C

## ELECTRICAL CHARACTERISTICS

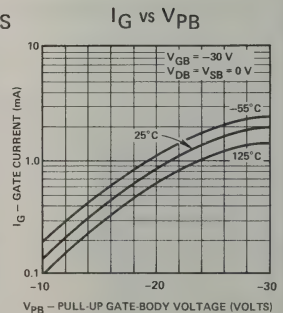
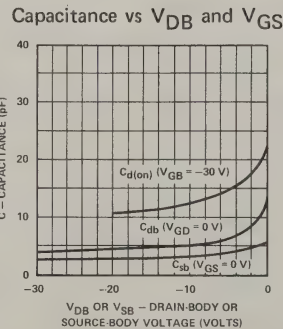
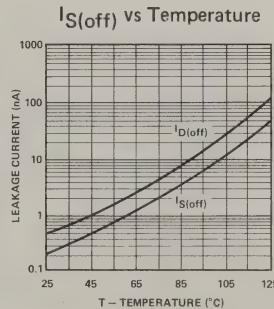
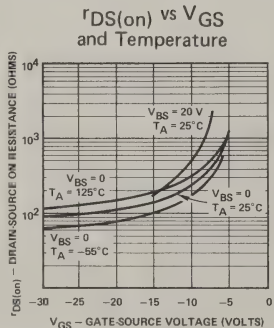
All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC		MAX LIMITS						UNIT	TEST CONDITIONS, UNLESS NOTED: V <sub>DB</sub> = 0, V <sub>PB</sub> = 0			
		A SUFFIX			B SUFFIX							
		-55°C	25°C	125°C	-20°C	25°C	85°C					
1	DS(on)	Drain-Source	100	100	125	125	125	150	Ω	V <sub>DB</sub> = 0, V <sub>GD</sub> = -30 V	I <sub>S</sub> = -1 mA	
2		ON Resistance	200	200	250	250	250	300		V <sub>DB</sub> = -10 V, V <sub>GD</sub> = -20 V		
3			450	450	600	500	500	600		V <sub>DB</sub> = -20 V, V <sub>GD</sub> = -10 V		
4	I <sub>S(off)</sub>	Source OFF		-0.5	-500		-5	-500	nA	V <sub>SD</sub> = -20 V, V <sub>GD</sub> = 0		
5		Leakage Current		-1	-1000		-10	-1000		V <sub>DS</sub> = -20 V, V <sub>GS</sub> = 0, V <sub>SB</sub> = 0		
6	I <sub>G(on)</sub>	Gate ON Current		-0.8 to -2.4			-0.8 to -2.4		mA	V <sub>GB</sub> = -30 V, V <sub>PB</sub> = -30 V		
7		IGSS		-0.5	-500		-5	-500		nA	V <sub>GB</sub> = -20 V	
8		V <sub>GS(th)</sub>	Gate-Source	-1.5 to -4.0	-1.5 to -4.0	-1.5 to -4.0	-1.5 to -4.0	-1.5 to -4.0		V	I <sub>D</sub> = -10 μA, V <sub>GD</sub> = 0, V <sub>SB</sub> = 0	
9	BV <sub>DSS</sub> Min	Drain-Source	-30	-30	-30	-30	-30	I <sub>D</sub> = -10 μA, V <sub>GS</sub> = 0, V <sub>SB</sub> = 0				
10	BV <sub>SDS</sub> Min	Source-Drain	-30	-30	-30	-30	-30	I <sub>S</sub> = -10 μA, V <sub>GD</sub> = 0				
11	BV <sub>GBS</sub> Min	Gate-Body	-35 to -90	-35 to -90	-35 to -90	-35 to -90	-35 to -90	I <sub>G</sub> = -10 μA				
12	BV <sub>PBS</sub> Min	Pull-Up Gate-Body	-35 to -90	-35 to -90	-35 to -90	-35 to -90	-35 to -90	I <sub>P</sub> = -10 μA, V <sub>GB</sub> = 0				
13	C <sub>gs</sub>	Gate-Source		1.8 Typ*			1.8 Typ*	pF	V <sub>DB</sub> = V <sub>SB</sub> = 0 Body Guarded	Drain Guarded	V <sub>GB</sub> = 0 f = 1 MHz	
14		C <sub>gd</sub>	Gate-Drain		1.8 Typ*		1.8 Typ*			Source Guarded		
15		C <sub>ds(off)</sub>	Drain-Source		0.4 Typ*		0.4 Typ*			Gate Guarded		
16		C <sub>sb</sub>	Source-Body		2 Typ*		2 Typ*			V <sub>DB</sub> = 0, V <sub>SB</sub> = -5 V		Gate and Drain Guarded
17		C <sub>db</sub>	Drain-Body		6 Typ*		6 Typ*			V <sub>SB</sub> = 0, V <sub>DB</sub> = -5 V		Gate and Source Guarded

\*Typical values are for DESIGN AID ONLY, not guaranteed and not subject to production testing.

MAB-C

## TYPICAL CHARACTERISTICS







**Siliconix**

Introduction	0
Interface	1
Telecommunications	2
Analog Switches	3
Analog Multiplexers	4
Multi-Channel FETs	5
<b>Linear</b>	<b>6</b>
A/D Converters	7
D/A Converters	8
Die Process & Topography	9
Burn-In Pin Connections	10
Package Data	11
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## LINEAR

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L161 .....	6-11
AN76-7 .....	6-16
Si1525B/27B, Si2525B/27B, Si3525B/27B .....	6-22

*Stresses listed under "Absolute Maximum Ratings" may be applied (one at a time) to devices without resulting in permanent damage. This is a stress rating only and not subject to production testing. Exposure to absolute maximum rating conditions for extended periods may effect device reliability.*

# Low-Power Triple Operational Amplifier

*designed for . . .*

- Instrumentation Amplifiers
- Buffer Amplifiers
- Voltage Comparators
- Low-Drift Sample and Hold Circuits
- Active Filters
- Battery-Powered Circuits

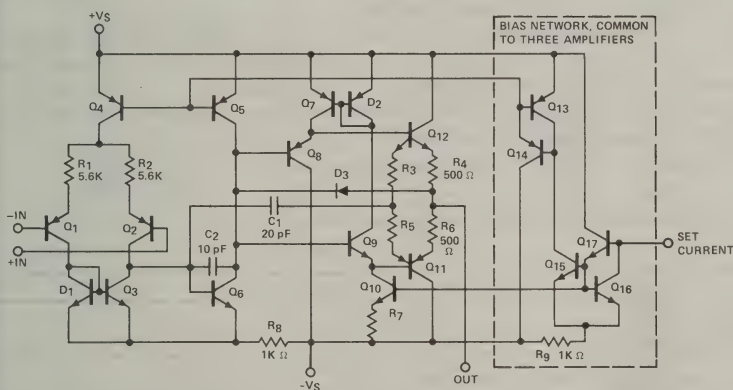
## BENEFITS

- Low Cost and Compact
  - 3 Amplifiers in One Package
- Easily Tailored to Optimize Circuit Performance
  - Programmed Supply Current
  - Operates with  $\pm 1.5$  V to  $\pm 15$  V
- Very Rugged
  - $\pm 30$  V Differential Input Voltage Range
  - Drives Large Capacitive Loads  $< 1000$  pF
  - Continuous Short Circuit Protection

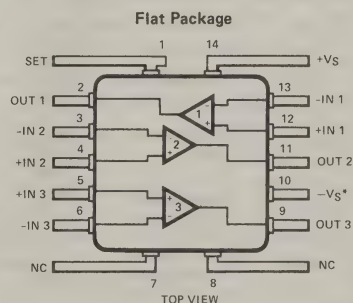
## DESCRIPTION

The L144 is a monolithic low-power triple operational amplifier stabilized for all feedback configurations and capacitive loads by internal gain compensation. Low power requirements permit high voltage operation across the rated temperature range, as well as battery operation from  $\pm 1.5$  V.

## SCHEMATIC DIAGRAM (One Amplifier)



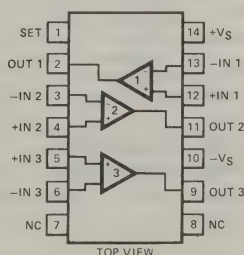
## PIN CONFIGURATIONS



\*COMMON TO SUBSTRATE AND BASE OF PACKAGE

**ORDER NUMBERS: L144AL OR L144BL  
SEE PACKAGE 5**

### Dual-In-Line Package



**ORDER NUMBERS: L144AP OR L144BP  
SEE PACKAGE 11**

**L144CJ  
SEE PACKAGE 7**

## ABSOLUTE MAXIMUM RATINGS

Supply Voltage	±18 V
Differential Input Voltage	±30 V
Input Voltage* (A Suffix)	±18 V
(C Suffix)	±15 V
Output Short Circuit Duration**	Indefinite
Operating Temperature (A Suffix)	-55 to +125°C
(B Suffix)	-20 to +85°C
(C Suffix)	0 to +70°C
Storage Temperature (A and B Suffix)	-65 to 150°C
(C Suffix)	-65 to 125°C
Lead Temperature (Soldering, 60 Sec)	300°C
Power Dissipation (Package)***	
Flat Package	750 mW
14 Pin DIP	825 mW
Plastic DIP	470 mW

\*For supply voltages < ±18 V, maximum input voltage is equal to the supply voltage.

\*\*Continuous short circuit is allowed for case temperatures to +125°C and ambient temperature to +70°C.

\*\*\*All leads welded or soldered to P.C. board. Derate 10 mW/°C for the flat package, 11 mW/°C for the 14 pin DIP above +75°C and 6.3 mW/°C above 25°C for the plastic DIP.

## ELECTRICAL CHARACTERISTICS

All DC parameters are 100% tested at 25°C. Lots are sample-tested for AC parameters and high and low temperature limits to assure conformance with specifications.

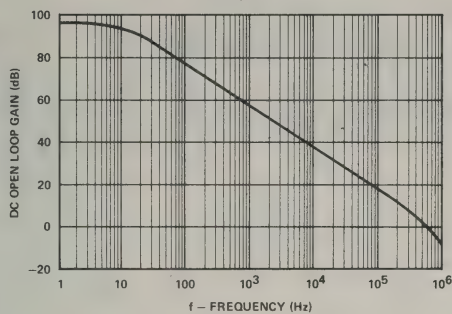
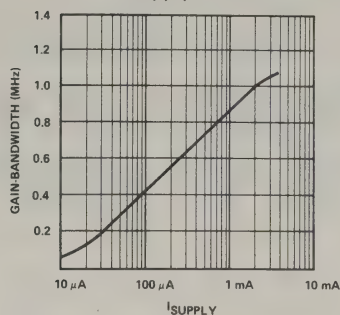
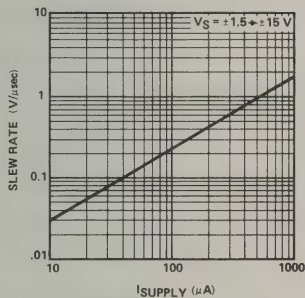
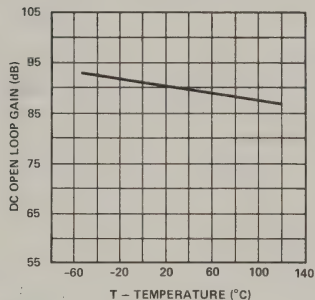
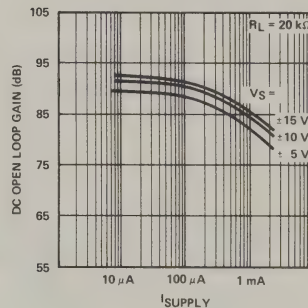
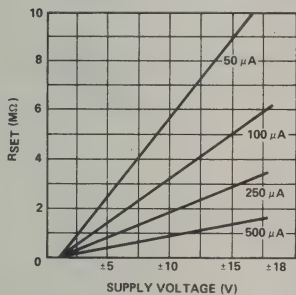
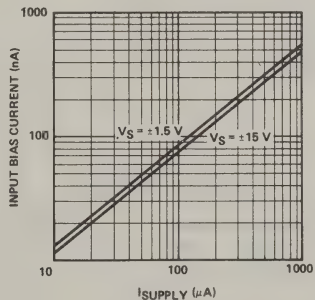
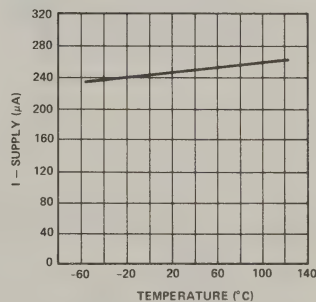
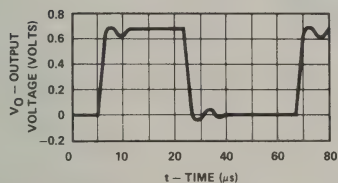
CHARACTERISTIC			L144A/B			L144C			UNIT	TEST CONDITIONS, UNLESS NOTED: V <sub>S</sub> = ±15 V, R <sub>L</sub> = 50 KΩ, R <sub>SET</sub> = 3 MΩ* Pin 1 to Pin 14
			-55°C/ -20°C	25°C	125°C/ 85°C	0°C	25°C	70°C		
1	V <sub>OS</sub>	Input Offset	Max	6	5	6		10	mV	R <sub>S</sub> ≤ 50K Ω
		Voltage	Typ**		1			1		
3	dV <sub>OS</sub> /dT	Average Temperature	Typ**		3.3			3.3	μV/°C	R <sub>S</sub> ≤ 50K Ω
		Coefficient of Input Offset Voltage								
4	I <sub>OS</sub>	Input Offset Current	Max		50			70	nA	
			Typ**		2			5		
6	I <sub>BIAS</sub>	Input Bias Current	Max	-200	-200		-250	-250		
			Typ**		-100			-125		
8	V <sub>OUT</sub>	Output Voltage	Min		±10			±10	V	
		Swing	Typ**		±14			±14		
10	I <sub>SC</sub>	Output Short	Typ**		±0.5			±0.4	mA	V <sub>S</sub> = ±1.5 V, R <sub>SET</sub> = 120K Ω
		Circuit Current	Max		15					
12	A <sub>VOL</sub>	DC Open Loop	Typ**		1.5			1.5	mV/mV	R <sub>L</sub> = 0
		Voltage Gain	Min							
13	S <sub>r</sub>	Slew Rate	Typ**	30	30	30	30	30	V/μs	
			Min	3.0	3.0	3.0	1.0	1.0		
15	f <sub>M</sub>	Unity Gain	Typ**		0.4			0.4	MHz	
		Bandwidth	Typ**		0.6			0.6		
17	CMRR	Common Mode	Typ**		-100			-100	dB	f = 100 Hz
		Rejection Ratio	Min		80			70		
19	PSRR	Power Supply	Typ**		90			80		V <sub>IN</sub> = ±12 V
		Rejection Ratio	Min		80			80		
22	I <sub>S</sub>	Source Current	Typ**		90			90	μA	Unity Gain V <sub>IN+</sub> = 0 on all amps
			Max		350			400		

\*I<sub>CC</sub> is adjustable. See typical characteristics.

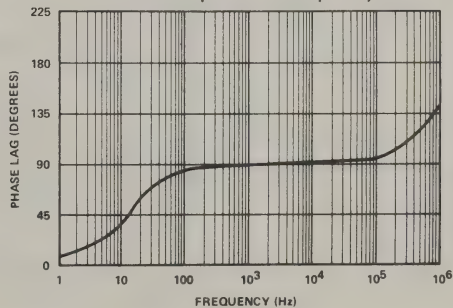
CMAC

\*\*Typical values are for DESIGN AIQ ONLY, not guaranteed and not subject to production testing.



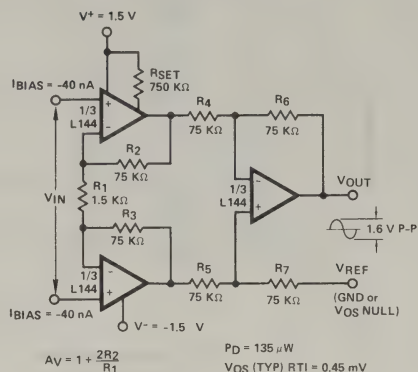
TYPICAL CHARACTERISTICS ( $T_A = 25^\circ\text{C}$ )Open Loop Gain vs  
FrequencyGain-Bandwidth Product  
vs Supply CurrentSlew Rate vs  
Supply CurrentDC Open Loop Gain  
vs TemperatureDC Open Loop Gain  
vs Supply CurrentSupply Current vs Set  
Resistor and Supply VoltageInput Bias Current vs  
Supply CurrentSupply Current vs  
TemperatureVoltage Follower  
Small Signal Pulse Response

Phase Response vs Frequency

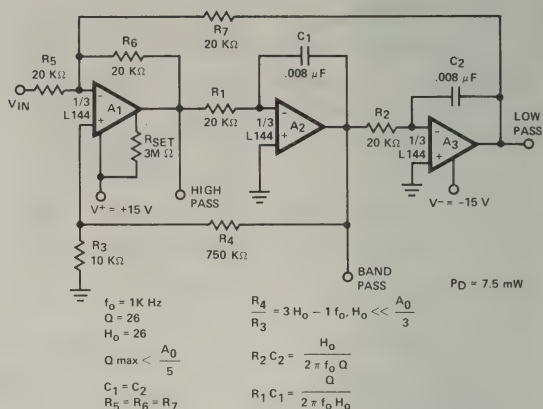


# APPLICATIONS

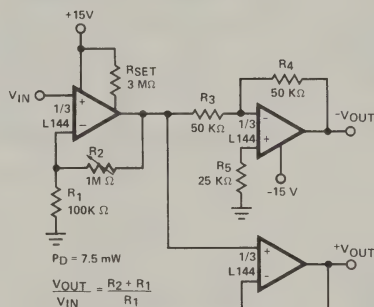
## Instrumentation Amplifier



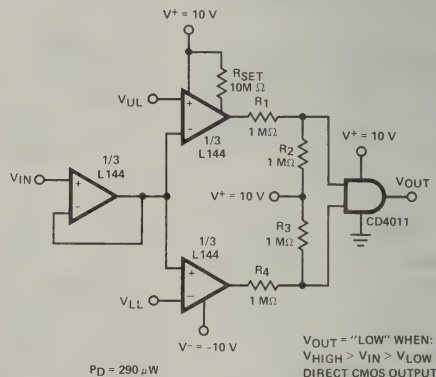
## Active Filter



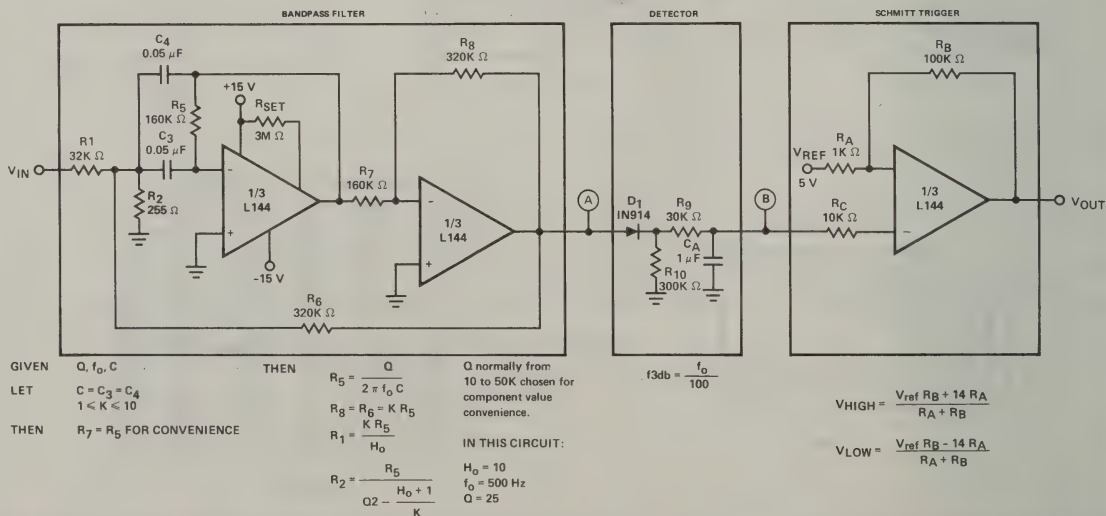
## Precision Phase Splitter



## Double-Ended Limit Comparator



## 500 Hz Tone Detector



# Function / Application of the L144 Programmable Micropower Triple Op Amp

## INTRODUCTION

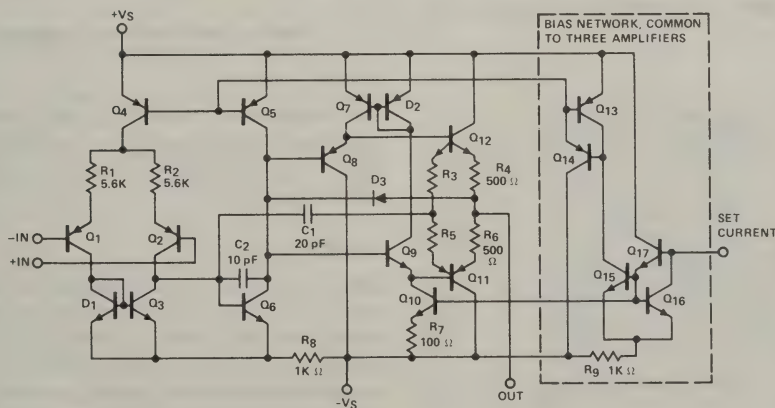
The L144 is a monolithic triple operational amplifier circuit with an external programming feature for power dissipation and input bias current control. It finds application in RC active filters, instrumentation amplifiers, micropower comparators, and numerous general signal processing circuits. The L144 is a practical industry standard op amp wherever low current drain, low voltage, low power, or very small physical size are the controlling criteria.

This Application Note describes the L144, how to program it, what the effects of slew rate limiting are, and some practical circuit applications.

The L144 has three operational amplifiers programmed by one external current setting resistor. It operates from power

supplies ranging from  $\pm 18\text{ V}$  to as low as  $\pm 1.5\text{ V}$  with quiescent supply currents of from  $10\text{ }\mu\text{A}$  to greater than  $1\text{ mA}$  independent of supply voltage. The schematic shown in Figure 1 reveals a general-purpose PNP input transistor op amp with an outstanding difference. The master bias current is not set by an internal resistor strung from  $V^+$  to  $V^-$ , but is brought out to an external pin. This allows the user to determine the operating currents of each stage through a system of current mirrors. Of special interest to the designer are the equal collector currents of  $Q_1$  and  $Q_2$ , which are derived from the output of  $Q_4$ . These collector currents, divided by a beta of approximately 50, determine the input bias currents for each amplifier. The ratio between the set current and the collector current of  $Q_4$  is unity, which allows one to program the input bias current simply by changing the set current input of the device.

ONE AMPLIFIER

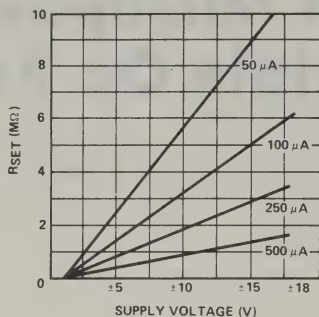


L144 Schematic  
Figure 1

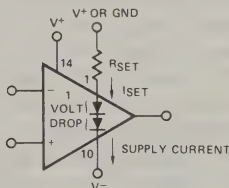


## Input Bias Current and Supply Current

The relationship between supply current, supply voltage, and the setting resistor is shown in the graph and set current model of Figure 2. The two diodes of the set current model correspond to the base-emitter junctions of  $Q_{16}$  and  $Q_{17}$ .



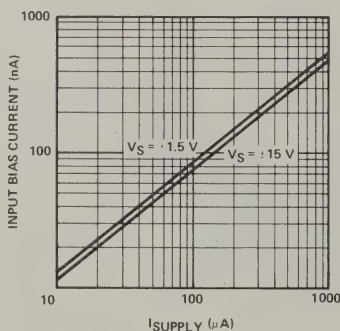
L144 SET CURRENT MODEL



Supply Current vs Bias Resistor and Supply Voltage  
Figure 2

Figure 3 shows the essentially linear relationship between input bias current and total quiescent supply current for the L144. The low input bias currents at low supply current levels allow the L144 to maintain good input specifications even with the large feedback and load resistor values normally encountered in micropower applications.

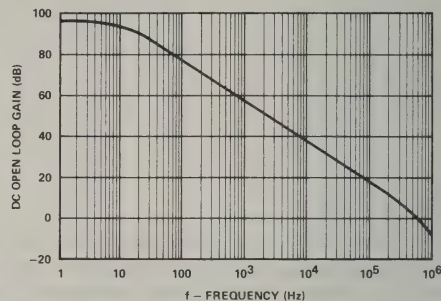
The slightly lower input bias currents at the higher supply voltages are due to the narrower base width and higher beta encountered at  $V_S = \pm 15$  V.



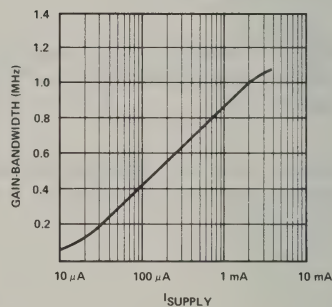
Input Bias Current vs Supply Current  
Figure 3

## Frequency Response

At the data sheet standard supply current of 250  $\mu A$  the typical Bode plot is as shown in Figure 4. The low frequency gain of approximately 95 dB rolls into a uniform -20 dB/decade slope until after the 0 dB unity gain crossing point. The variation of open loop gain with temperature is typically -2 dB per 100°C of temperature rise. The 600 kHz unity gain crossover gives a gain bandwidth product (GBWP) of 600,000. Figure 5 shows the variation of GBWP with supply current.



L144 Open Loop Gain vs Frequency  
Figure 4



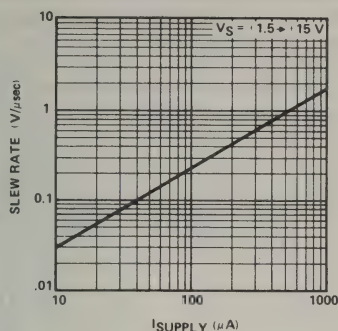
L144 Gain Bandwidth Product vs Supply Current  
Figure 5

The vertical axis is linear whereas the horizontal  $I_{CC}$  axis is logarithmic, demonstrating that the GBWP does vary with  $I_{CC}$ , but at much less than the 1-to-1 ratio observed for other parameters.

## Slew Rate

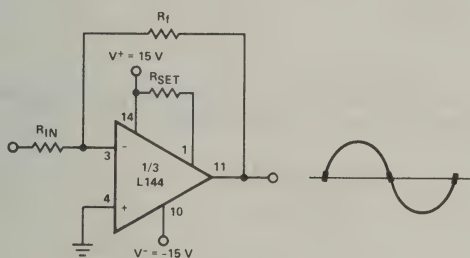
Slew rate is almost a direct function of supply current as shown in Figure 6. This follows from the fact that slew rate limiting is actually caused by the finite limits of the internal current sources (which charge and discharge the second stage compensation capacitor) varying with the externally-determined set current. An amplifier output changes from the small signal response shown on the Bode plot to a slew-rate-limited response when the rate of change of the output voltage exceeds the rate of change determined by slew rate limit of the amplifier. Since the maximum rate of change of





Slew Rate Limits vs Supply Current  
Figure 6

a sine wave is a function of peak amplitude it is possible to trade maximum frequency for peak signal amplitude when operating at low power dissipation levels. Figure 7 shows the derivation<sup>1</sup> of an equation relating slew rate  $S_r$ , sine wave amplitude  $V_{PEAK}$ , and frequency. The zero crossing of a sine wave is the point of maximum rate of change as shown after the derivative is taken and maximized. In both of the examples shown the maximum undistorted operating frequency is kept constant while juggling power dissipation, slew rate, and peak amplitude in an engineering tradeoff.



$$V_{OUT} = V_{peak} \sin 2\pi ft$$

$$\frac{dV_{OUT}}{dt} = V_{peak} 2\pi f \cos 2\pi ft$$

$$\left. \frac{dV_{OUT}}{dt} \right|_{t=0} = V_{peak} 2\pi f$$

$$S_r = \left. \frac{dV_{OUT}}{dt} \right|_{\max} = V_{peak} 2\pi f_{\max}$$

$$I_{SUPPLY} = 820 \mu A, S_r = 1.5 V/\mu sec$$

$$I_{SUPPLY} = 60 \mu A, S_r = 0.15 V/\mu sec$$

$$P_D = 24 mW, V_{peak} = 10 V$$

$$P_D = 1.8 mW, V_{peak} = 1 V$$

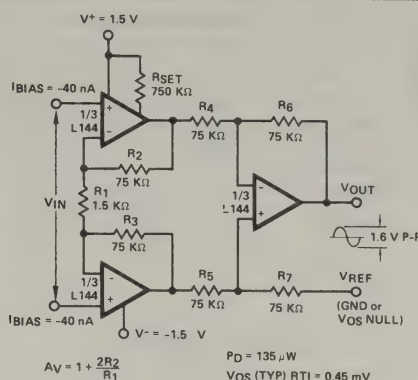
$$f_{\max} = \frac{S_r}{V_{peak} 2\pi} = 24 KHz$$

$$f_{\max} = \frac{S_r}{V_{peak} 2\pi} = 24 KHz$$

Slew Rate Limiting  
Figure 7

## Instrumentation Amplifier

Figure 8 shows a single L144 chip used to construct a three-amplifier classical instrumentation amplifier. The entire circuit consumes only 135  $\mu W$  of power from a  $\pm 1.5 V$  power supply. With a gain of 101 the instrumentation amplifier is ideal in sensor interface and biomedical preamplifier applications.

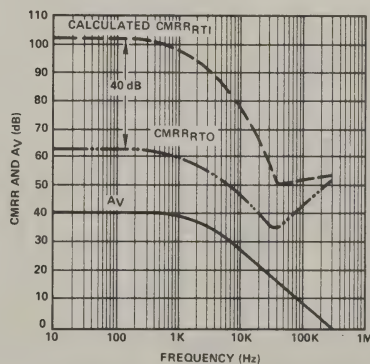


L144 Instrumentation Amplifier  
Figure 8

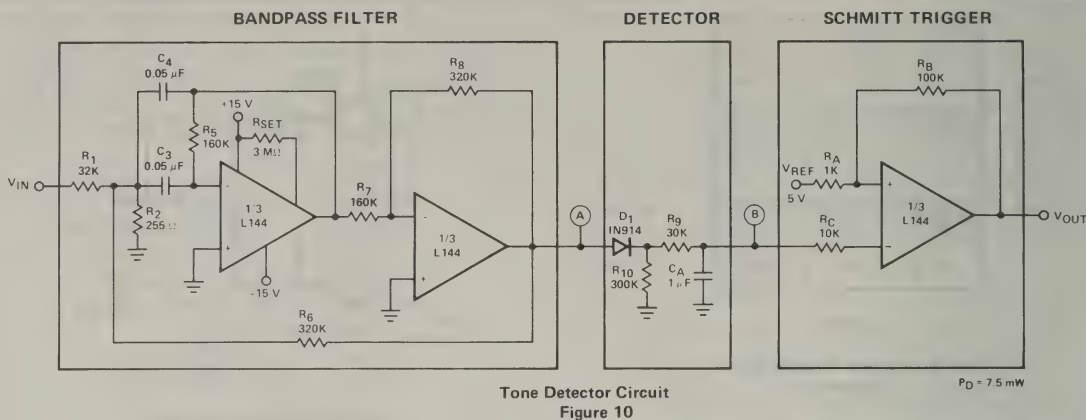
The first stage provides all of the gain while the second stage is used to provide common mode rejection and double-ended to single-ended conversion. The resistor  $R_1$  determines the gain of the circuit according to the equation:

$$A_V = 1 + \frac{2R_2}{R_1} \quad (1)$$

The reference point at the base of  $R_7$  can be used to determine the quiescent output voltage when there is no differential input voltage. This provides an easy single point to zero any net offset voltage (typically 0.45 mV referred to input) and/or to insert a trim resistor to improve common mode rejection ratio (CMRR). The CMRR depends heavily on the match between  $R_4/R_6$  and  $R_5/R_7$  and can be nulled if  $R_7$  is broken into a resistor and a small-value trim potentiometer. Figure 9 shows the voltage gain and CMRR versus frequency for a typical instrumentation amplifier. The upper curve shows a calculated CMRR referred to input. The falloff and final rise in CMRR is due to the mismatch in gain rolloff between amplifiers in the first stage followed by a falloff in gain and consequent increase in rejection of the second stage.



Common Mode Rejection Ratio and Gain vs Frequency  
Figure 9



Tone Detector Circuit  
Figure 10

### Tone Detector

Another example of a single L144 providing the amplifiers for an entire system is shown in Figure 10. This tone detector circuit is made up of a two-amplifier multiple feedback bandpass filter followed by an AC-to-DC detector section and a Schmitt Trigger. The bandpass filter (with a Q of 25) passes only 500 Hz inputs which are in turn rectified by  $D_1$  and filtered by  $R_9$  and  $C_A$ . This filtering action in combination with the trigger level of 5 V for the Schmitt device insures that at least 55 cycles of 500 Hz input must be present before the output will react to a tone input. The actual integrating capacitor waveform shown in Figure 11 was taken with a 1 volt peak 500 Hz sine wave input. The ratio between capacitor  $C_A$  charge and discharge is 1:11, due to resistors  $R_9$  and  $R_{10}$ .

For frequencies other than the 500 Hz center frequency shown in the example the relevant bandpass filter<sup>2</sup> equations are:

$$\text{GIVEN: } Q, f_0, H_0 \text{ (Q normally from 10 to 50)} \quad (2)$$

$$\begin{aligned} \text{LET: } C &= C_3 = C_4 \\ 1 &\leq k \leq 10 \text{ (k chosen for component} \\ &\quad \text{value convenience)} \end{aligned} \quad (3)$$

$$\text{THEN: } R_7 = \frac{Q}{2\pi f_0 C} \quad (4)$$

$$R_7 = R_5 \quad (5)$$

$$R_1 = \frac{k R_7}{H_0} \quad (6)$$

$$R_2 = \frac{R_7}{Q^2 - \frac{H_0 + 1}{k}} \quad (7)$$

$$R_8 = k R_7 = R_6 \quad (8)$$

In the example shown in Figure 10 the chosen value of  $k = 2$  and the passive components used resulted in a measured Q of 23.1. The center frequency of 495.7 Hz and  $H_0$  of 9.9 were close to the calculated values of 500 Hz and 10.

The detector RC was designed to have a 3 dB down frequency of:

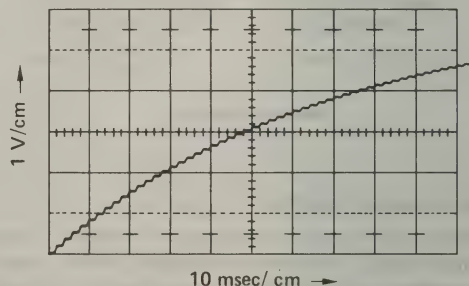
$$f_{3dB} = \frac{f_0}{100} \quad (9)$$

while the Schmitt trigger operated around the reference voltage with trip points determined by:

$$V_{HIGH} = \frac{V_{REF} R_B + 14 R_A}{R_A + R_B} \quad (10)$$

$$V_{LOW} = \frac{V_{REF} R_B - 14 R_A}{R_A + R_B} \quad (11)$$

where  $\pm 14$  V is the output swing with  $\pm 15$  V supplies. The measured trip points agreed with the calculated values of 5.089 V and 4.81 V within 0.2% in the circuit of Figure 10.



Detector Output Voltage vs Time  
Figure 11

### 3 Amplifier Active Filter

The active filter shown in Figure 12 is a state variable filter with band-pass, high-pass and low-pass outputs. It is a classical analog computer method of implementing a filter using three amplifiers and only two capacitors. With the L144 triple op amp it becomes cost-effective to use this configuration with its attendant high Q values and low sensitivities.<sup>3</sup> The practical maximum value of Q is:

$$Q_{\max} = \frac{A_{f0}}{3} \quad (12)$$

where  $A_{f0}$  is the open loop gain of amplifier  $A_1$  at the resonant frequency.

The controlling design equations are:

$$\text{GIVEN: } Q, f_0, \text{ and } H_0 \text{ (bandpass output)} \quad (13)$$

$$\text{LET: } R_5 = R_6 = R_7 \quad (\text{Chosen for component value convenience}) \quad (14)$$

$$C_1 = C_2$$

$$\text{THEN: } \frac{R_4}{R_3} = 3 H_0 - 1 \text{ for } H_0 \ll \frac{A_{f0}}{3} \quad (15)$$

$$R_2 C_2 = \frac{H_0}{2\pi f_0 Q} \quad (16)$$

$$R_1 C_1 = \frac{Q}{2\pi f_0 H_0} \quad (17)$$

The design example shown in Figure 12 was calculated as follows:

$$\begin{aligned} \text{LET: } Q &= 26 \\ f_0 &= 1 \text{ kHz} \\ H_0 &= 26 \\ R_5 &= R_6 = R_7 = 20 \text{ k} \\ C_1 &= C_2 = .008 \mu\text{F} \\ R_3 &= 10 \text{ k} \end{aligned} \quad (18)$$

$$\text{THEN: } R_4 = (3H_0 - 1) R_3 = 770 \text{ k} \approx 750 \text{ k} \quad (19)$$

$$R_2 = \frac{H_0}{2\pi f_0 Q C_2} = 19.9 \text{ k} \approx 20 \text{ k} \quad (20)$$

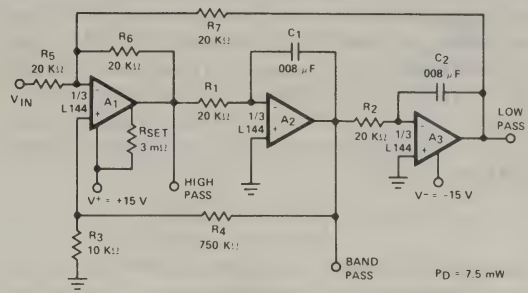
$$R_1 = \frac{Q}{2\pi f_0 H_0 C_1} = 19.9 \text{ k} \approx 20 \text{ k} \quad (21)$$

giving an actual calculated  $f_0$  and  $H_0$  of

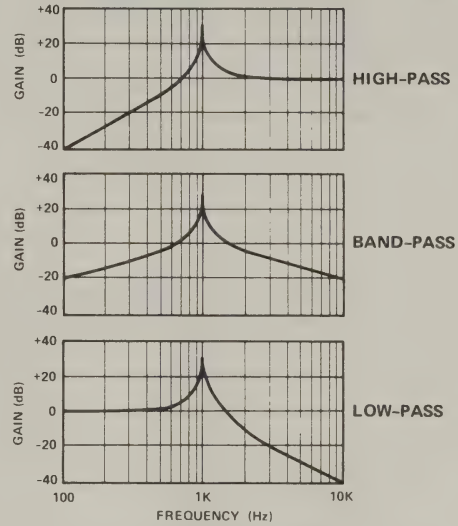
$$H_0 = 1/3 \left( 1 + \frac{R_4}{R_3} \right) = 25.3 \quad (22)$$

$$f_0 = \frac{Q}{2\pi R_1 C_1 H_0} = \frac{H_0}{2\pi R_2 C_2 Q} = 994.7 \text{ Hz} \quad (23)$$

The measured values of Q,  $H_0$ , and  $f_0$  using 1% components were 26.9, 26.3 and 996 respectively. Figure 13 shows the Bode plots of the high-pass, band-pass, and low pass outputs.



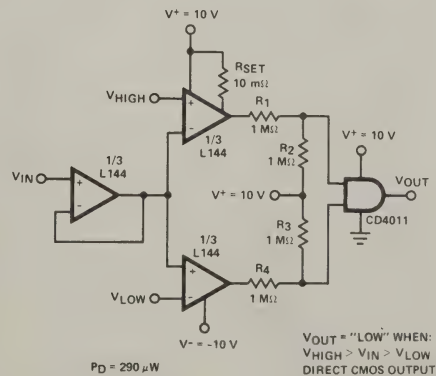
3 Amplifier Active Filter  
Figure 12



Bode plots of Active Filter Output  
Figure 13

### Micropower Double-Ended Limit Detector

The double-ended limit detector shown in Figure 14 uses three sections of an L144 and a DC4011 type CMOS NAND



Micropower Double-Ended Limit Detector  
Figure 14

gate to make a very low power voltage monitor. If the input voltage  $V_{IN}$  is above  $V_{HIGH}$  or below  $V_{LOW}$  the output will be a logical high. If (and only if) the input is between the limits will the output be low. The  $1\text{ M}\Omega$  resistors  $R_1$ ,  $R_2$ ,  $R_3$  and  $R_4$  translate the bipolar  $\pm 10\text{ V}$  swing of the op amps to a 0 to 10 V swing acceptable to the ground-referenced CMOS logic.

Total power dissipation is typically  $290\text{ }\mu\text{W}$  while in limit and  $330\text{ }\mu\text{W}$  while out of limit. Within the  $\pm 9\text{ V}$  input range of the circuit the comparator resolution is typically  $2\text{ mV}$  with the offset adjust determined by trimming  $V_{HIGH}$  and  $V_{LOW}$ . Since the L144 is operating at only  $14.5\text{ }\mu\text{A}$  of supply current the slew rate is a corresponding low  $.063\text{ V}/\mu\text{sec}$ .

## CONCLUSION

The preceding practical circuit examples are intended to show a few of the many possible applications of the L144 micropower triple op amp.

## REFERENCES

1. M.K. Vander Kooi, "Slew Rate Limiting of IC Op Amp is Easy to Predict and to Avoid," EDN, October, 1972; pp. 36-37.
2. J.G. Graema, G.E. Tobey, and L.P. Huelsman; "Operational Amplifiers Design and Application," McGraw-Hill Co., New York, N.Y., 1971, pp.293-295.
3. S.K. Mitra, "Active Inductorless Filters," IEEE Inc., New York, N.Y., 1971, pp. 74-78.



# Micropower Quad Comparator

*designed for . . .*

**Siliconix**

**L161**

- Voltage Comparators
- Window Comparators
- Level Detectors
- CMOS Line Receivers
- Oscillators
- Ramp Generators
- Phase Comparators
- Battery Powered Circuits

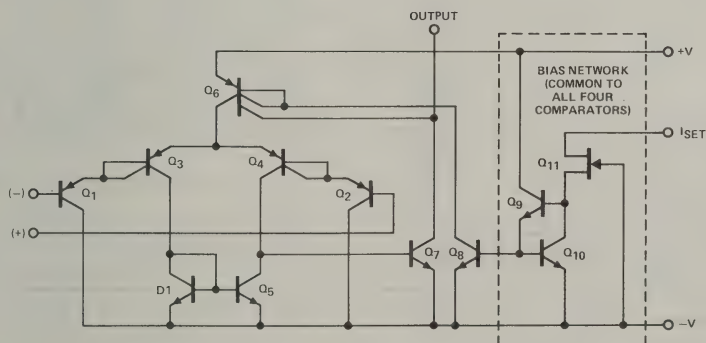
## BENEFITS

- **Minimizes System Power Requirements**
  - Operates on 15  $\mu$ W
- **Reduces External Component Requirements**
  - Programmable Output Drive Capability
  - Direct Wire-OR of Output
  - Input Sensing Near Ground
  - Direct CMOS Logic Compatibility
- **Easily Tailored to Your System**
  - Single Programming Resistor Simultaneously Alters Supply Current, Input Bias Current, Slew Rate and Power Consumption
- **Minimizes Number of Supply Voltages in Your System**
  - Operates with  $\pm 1.0$  V to  $\pm 18$  V
  - Single Supply Operation

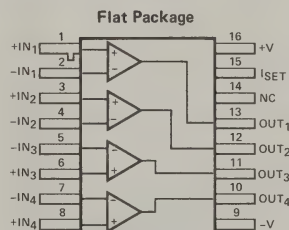
## DESCRIPTION

The L161 is a monolithic quad micropower comparator circuit, with an external control for varying supply current, input bias current and output current drive. This is accomplished by a single resistor connected to  $V^+$  which controls the bias current to  $Q_{10}$  which, via a series of current mirrors, supplies bias to the differential amplifier. The L161 finds applications in areas where low powered battery operation and CMOS compatibility are required. The ability to control comparator characteristics makes this a very versatile device.

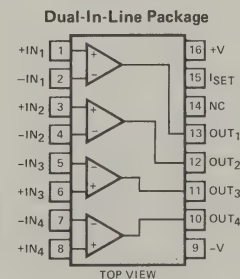
## SCHEMATIC DIAGRAM (ONE COMPARATOR)



## PIN CONFIGURATIONS



TOP VIEW  
ORDER NUMBERS L161AL  
OR L161BL  
SEE PACKAGE 17



TOP VIEW  
ORDER NUMBERS L161AP  
OR L161BP  
SEE PACKAGE 12  
ORDER NUMBER L161CJ  
SEE PACKAGE 8

6

**Linear**

**ABSOLUTE MAXIMUM RATINGS\***

Supply Voltage . . . . .	±18 V
Differential Input Voltage . . . . .	±30 V
Input Voltage* (A Suffix) . . . . .	±18 V
(B Suffix) . . . . .	±18 V
Output Short Circuit Duration** (Indefinite)	
Operating Temperature (A Suffix) . . . . .	-55 to +125°C
(B Suffix) . . . . .	-20 to +85°C
(C Suffix) . . . . .	0 to +70°C
Storage Temperature (A and B Suffix) . . . . .	-65 to +150°C
(C Suffix) . . . . .	-65 to +125°C
Power Dissipation***	
Flat Package . . . . .	750 mW
16 Pin DIP (Side Braze) . . . . .	900 mW

16 Pin Plastic DIP . . . . . 470 mW

\* For supply voltages  $< \pm 18$  V, maximum input voltage is equal to supply voltage

\*\* Continuous short circuit current is allowed for case temperature to +125°C and ambient temperature to +70°C

\*\*\* All leads welded or soldered to PC board. Derate 10 mW/°C above 75°C for the flat package, 12 mW/°C above 75°C for the sidebraze DIP and 6.3 mW/°C above 25°C for the plastic DIP.

**ELECTRICAL CHARACTERISTICS**

All DC parameters are 100% tested at 25°C. Lots are sample tested for AC parameters and high and low temperature limits to assure conformance with specifications.

**Low Power Characteristics**

Characteristics				L161A			L161B/C			Unit	Test Conditions, Unless Otherwise Noted: V <sub>S</sub> = ±3 V, I <sub>SET</sub> = 10 μA, R <sub>L</sub> = 10M Ω C <sub>L</sub> = 10 pF			
				-55°C	25°C	+125°C	-20°C/ 0°C	25°C	+85°C/ 70°C					
1	INPUT	V <sub>OS</sub>	Input Offset Voltage	Max	5.0	3.0	5.0		6.0	mV				
2			Typ*			1.0			1.0					
3		I <sub>OS</sub>	Input Offset Current	Max		20			25	nA				
4			Typ*			1.0			1.0					
5		I <sub>BT</sub>	Input Bias Current, Total	Max		100			200	nA				
6			Typ*			20			20					
7	OUTPUT	A <sub>VOL</sub>	DC Open Loop Voltage Gain	Min	10	20	20	5	10	10	V/mV			
8			Typ*	25	30	35	25	30	35					
9		V <sub>OL</sub>	Low Output Voltage	Min		-2.6			-2.6	V	R <sub>L</sub> = 20K Ω			See Note 1
10			Typ*		-2.95			-2.95	R <sub>L</sub> = 20K Ω					
11		V <sub>OH</sub>	High Output Voltage	Min		2.5			2.5	V	R <sub>L</sub> = 200K Ω			
12			Typ*		2.9			2.9	R <sub>L</sub> = 200K Ω					
13	DYNAMIC	CMR	Common Mode Range	Typ*		+1.3/ -3.0			+1.3/ -3.0	V				
14		t <sub>r</sub>	Response Time	Typ*		5.0			5.0	μsec	100 mV Overdrive			
15		CMRR	Common Mode Rejection Ratio	Min		75			75	dB	V <sub>IN</sub> = CMR			
16			Typ*		90			90						
17		PSRR	Power Supply Rejection Ratio	Min		65			65	dB				
18			Typ*		80			80						
19	SUPPLY	I <sub>S</sub>	Supply Current	Max	300	300	350	300	300	350	μA	All Inputs Grounded		
20			Typ*		210			210				R <sub>L</sub> = ∞		

IBAJ

\*Typical values are for Design Aid only, not guaranteed and not subject to production testing.

**NOTE:**

- The output current drive of the L161 is non-symmetrical. This facilitates the wire-ORing of two comparator outputs. The output pulldown current pulldown current capability is typically 75–150 times the pullup current.

ELECTRICAL CHARACTERISTICS (Cont'd)

High Power Characteristics

Characteristics			L161A			L161B/C			Unit	Test Conditions, Unless Otherwise Noted: $V_S = \pm 15\text{ V}$ , $I_{SET} = 100\text{ }\mu\text{A}$ , $R_L = 2\text{ M}\Omega$ $C_L = 10\text{ pF}$	
			-55°C	25°C	+125°C	0°C/ -20°C	25°C	70°C/ +85°C			
1	INPUT	$V_{OS}$ Input Offset Voltage	Max 6.0	3.0	6.0		6.0		mV		
2			Typ*	1.5			1.5				
3		$I_{OS}$ Input Offset Current	Max	60			90		nA		
4			Typ*	5.0			5.0				
5		$I_{BT}$ Input Bias Current, Total	Max	400	500		800		nA		
6			Typ*	100			100				
7	OUTPUT	$A_V$ Voltage Gain	Min 25.0	50	50	15	30	30	V/mV	See Note 1	
8			Typ*	75.0	100	100	75	100			
9		$V_{OL}$ Low Output Voltage	Min	-14.6			-14.6		V		
10			Typ*	-14.9			-14.9				
11		$V_{OH}$ High Output Voltage	Min	14.5			14.5		V		
12			Typ*	14.9			14.9				
13	DYNAMIC	CMR Common Mode Range	Typ*	+13/-15.0			+13/-15.0		V	100 mV Overdrive, $C_L = 10\text{ pF}$	
14		$t_r$ Response Time	Typ*	1.0			1.0		$\mu\text{sec}$		
15		CMRR Common Mode Rejection Ratio	Min	75			75		dB	$V_{IN} = \text{CMR}$	
16	SUPPLY		Typ*	90			90				
17		PSRR Power Supply Rejection Ratio	Min	65			65		dB		
18			Typ*	80			80			All Inputs Grounded $R_L = \infty$	
19		$I_S$ Supply Current	Max	4000	3500	3750	4000	3500	$\mu\text{A}$		
20			Typ*	2100			2100				

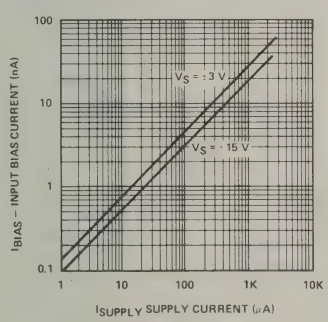
\*Typical values are for Design Aid only, not guaranteed and not subject to production testing.

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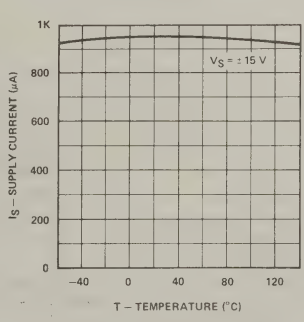
NOTE:  
1. Set current ( $I_{SET}$ ) and supply current ( $I_{SUPPLY}$ ) can be determined by the following formulas:  $I_{SET} = \frac{[(+V) - (2V_{BE}) - (-V)]}{R_{SET}}$ ;  
 $I_{SUPPLY} \approx 21 \times I_{SET}$ .

TYPICAL CHARACTERISTICS ( $T_A = 25^\circ\text{C}$ ,  $V_{SUPPLY} = \pm 15\text{ V}$  unless otherwise noted)

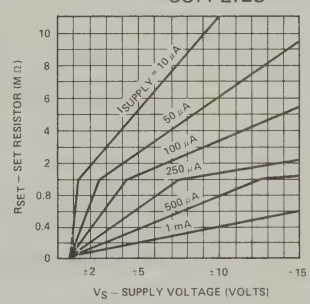
Input Bias Current vs Supply Current



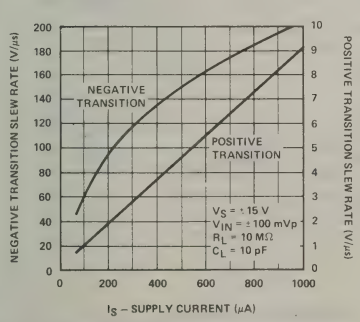
Supply Current vs Temperature



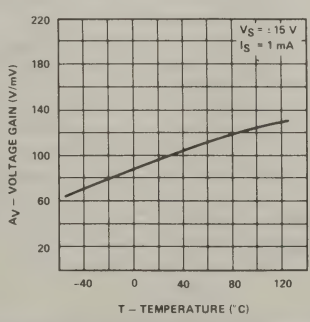
RSET vs VSUPPLY for Various ISET



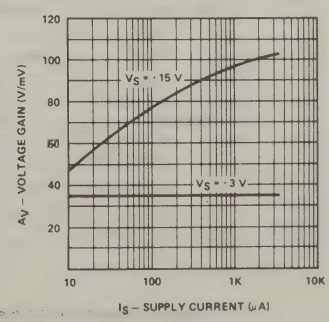
Slew Rate vs Supply Current



Voltage Gain vs Temperature



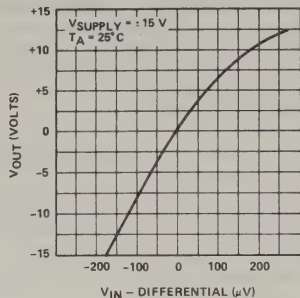
Voltage Gain vs Supply Current



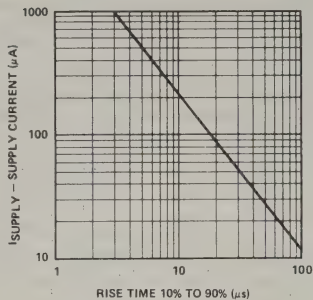


TYPICAL CHARACTERISTICS (Cont'd) ( $T_A = 25^\circ\text{C}$ ,  $V_{\text{SUPPLY}} = \pm 15\text{ V}$  unless otherwise noted)

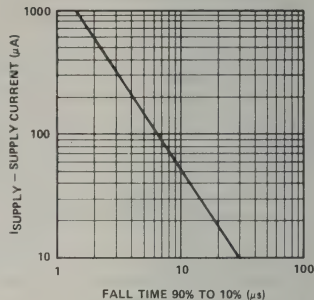
Transfer Characteristic



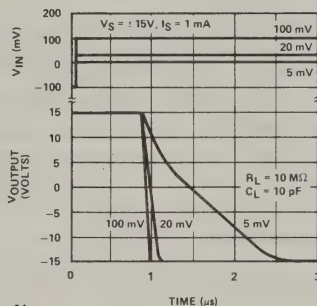
Rise Time vs Supply Current with One CMOS Load



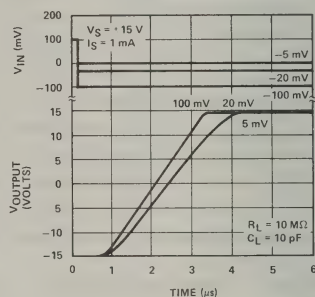
Fall Time vs Supply Current with One CMOS Load



Response Time vs Input Overdrive Negative Transition



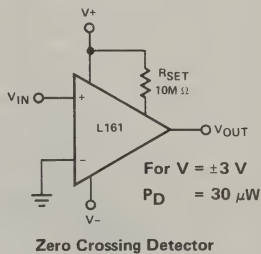
Response Time vs Input Overdrive Positive Transition



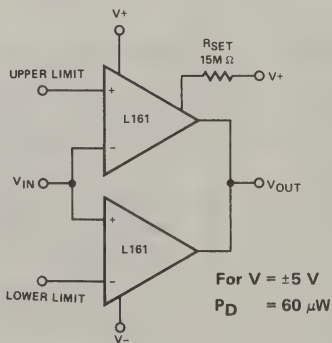
Note:

The output current drive of each comparator in the L161 is non-symmetrical. The pull-up current is typically  $2[V_+ - 1 - (V_-)/R_{\text{SET}}]$  and the pull-down current capability is typically from 75 to 150 times the pull-up current.

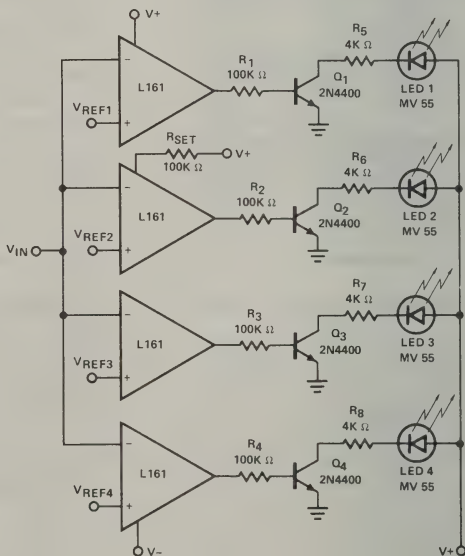
APPLICATIONS



Zero Crossing Detector



Double Ended Limit Detector



Voltage Level Detector



# Linear

# Function/Application of the L161

## Micropower Comparator

### INTRODUCTION

The L161 is a monolithic quad micropower comparator with an external control for varying its AC and DC characteristics. The variation of a single programming resistor will simultaneously alter parameters such as supply current, input bias current, slew rate, output drive capability, and gain. By making this resistor large, operation at very small supply current levels and power dissipations — typically in the low microwatt region — is possible. The L161 is therefore ideal for systems requiring minimum power drain, such as battery-powered instrumentation, aerospace systems, CMOS designs, and remote security systems.

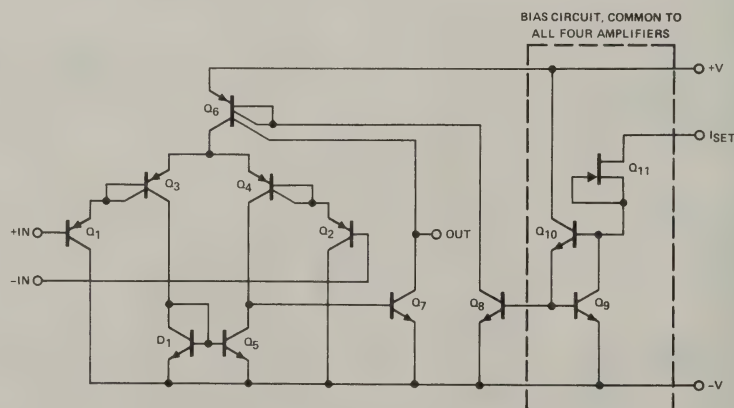
### Description

The L161 is fabricated on a 48 x 54 mil chip using standard bipolar processing. The circuit (Figure 1) is composed of five major blocks — four comparators and a common bias

network.  $Q_1$ - $Q_6$  and  $D_1$  form a darlington differential amplifier with double-to-single ended conversion.  $Q_6$  is a dual current source whose outputs are exactly twice the current flowing through  $Q_8$ . The collector current of  $Q_8$  is a function of the current supplied externally to  $Q_9$ - $Q_{10}$ , which in turn is known as the set current or  $I_{SET}$ . This set current is established by a resistor connected between the  $I_{SET}$  terminal and a voltage source, most commonly the positive supply.  $Q_{11}$  prevents excessive current from flowing through  $Q_9$  and  $Q_{10}$  in the event the  $I_{SET}$  terminal is shorted to the positive supply; it has no effect on circuit operation under normal conditions.

The set current can be expressed as:

$$I_{SET} = \frac{[(+V) - (2V_{BE}) - (-V)]}{R_{SET}} \quad (1)$$



Schematic of One Channel of the L161  
Plus the Common Bias Network  
Figure 1

where +V is the voltage to which the control resistor is connected, -V is the negative supply voltage,  $V_{BE}$  is the base emitter drop of  $Q_9$  or  $Q_{10}$  (about 0.7 V), and  $R_{SET}$  is the value of the external control resistor or set resistor. Equation 1 is simply a derivative of ohms law. There is also an analytical relationship between  $I_{SET}$  and the total supply current:

$$\begin{aligned}
 I_{SUPPLY} &= [I_{SET} \text{ (current sourced by } Q_6 \text{ to } Q_8) \\
 &\quad + 2 I_{SET} \text{ (current sourced to the differential amplifier by } Q_6) \\
 &\quad + 2 I_{SET} \text{ (current sourced to the comparator output by } Q_6) \\
 &\quad \times 4 \text{ (the total numbers of comparators)} \\
 &\quad + I_{SET} \text{ (current sourced through } Q_{11}, \\
 &\quad Q_{10}, \text{ and } Q_9 \text{ to } -V) \\
 &= [I_{SET} + 2 I_{SET} + 2 I_{SET}] \times 4 + I_{SET} \\
 &= 21 I_{SET}
 \end{aligned}$$

The output current pulldown capability ( $I_{OL}$ ) of the L161 is about 2 orders of magnitude greater than the high output drive current, ( $I_{OH}$ ), which allows wire-ORing the outputs.  $I_{OH}$  is simply the current sourced by  $Q_6$ :

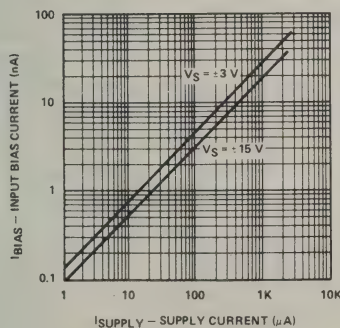
$$I_{OH} = 2 \times I_{SET} \quad (3)$$

$I_{OL}$  is found by multiplying the current sourced by the collector of  $Q_6$  by the gain of  $Q_7$ :

$$I_{OL} = \beta(Q_7) \times 2 I_{SET} \quad (4)$$

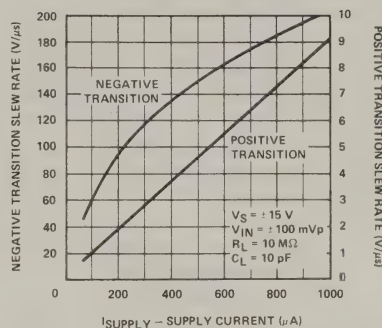
The beta of  $Q_7$  is about 75-150.

Input bias current is a function of the betas of input devices  $Q_1$ - $Q_2$  and  $I_{SET}$ . This is difficult to express analytically because  $\beta$  varies greatly with both processing and collector current; however it is roughly proportional to the set current and can easily be determined experimentally (see Figure 2).

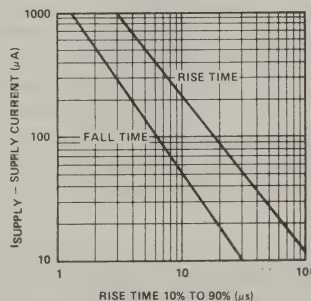


Input Bias Current vs Supply Current  
Figure 2

Gain varies logarithmically with changes in supply voltage and linearly with changes in set current. Primary causes are the decrease in output impedance of  $Q_7$  with decreasing supply voltage and an increase in transistor betas with increasing set current. Other AC parameters such as slew rate and transition time are also effected by set current; however current dependent parameters such as beta and chip capacitances make mathematical expressions imprecise. These relationships have been determined empirically and are presented in Figures 3 and 4.



Slew Rate vs Supply Current  
Figure 3

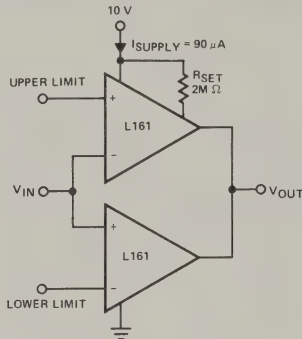


Rise and Fall Times vs Supply Current  
With One CMOS Load  
Figure 4

The designer's ability to program the key parameters of the L161 enables him to program just enough supply current to meet his design objectives. This coupled with the L161's performance using only microwatts of power makes it ideal for any micropower or battery-powered system, as well as a replacement for existing higher power comparators. The following applications illustrate the flexibility and unique capabilities of the L161.

## Micropower Applications

A classic comparator application is the double-ended limit detector or window comparator shown in Figure 5.  $V_{OUT}$  is high whenever the input voltage is within the two limits. Because the Darlington input stage extends the common-mode input range below the negative supply, the lower limit may be as low as  $-0.4$  V with the  $V_-$  terminal at ground. A comparison about ground is therefore possible with only one supply.

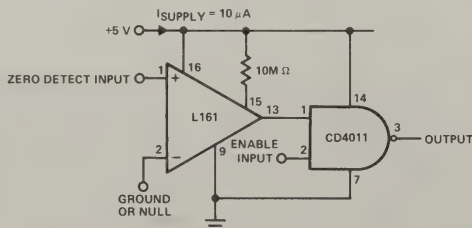


Double-Ended Limit Comparator  
With Wire OR'd Outputs  
Figure 5

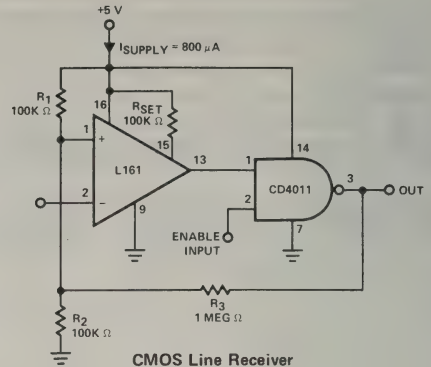
The L161 is especially suited for this application because of its wire OR capability; low output on either comparator will pull both outputs to ground. For this example a supply current of  $90 \mu\text{A}$  was chosen to provide a slew rate of about  $5 \text{ V}/\mu\text{s}$ . If greater output drive current or decreased transition times are needed, lower  $R_{SET}$ .

The zero crossing detector shown in Figure 6 is useful in sine wave squaring circuits and A/D converters. This circuit also takes advantage of the L161's ability to detect signals below its negative rail, so only a positive supply is needed. The positive input may either be grounded or connected to a nulling voltage which cancels input offsets and enables accuracy to within microvolts of ground. The CMOS output will switch to within a few millivolts of either rail for an input voltage change of less than  $200 \mu\text{V}$ .

The circuit in Figure 6 may be modified to produce a line receiver (Figure 7). The trip point is set half way between the supplies by  $R_1$  and  $R_2$ ;  $R_3$  provides over  $200 \text{ mV}$  of hysteresis to increase noise immunity. With  $800 \mu\text{A}$  of quiescent supply current the maximum frequency of operation is about  $300 \text{ kHz}$ . If response to TTL levels is desired, change  $R_2$  to  $39\text{K}$ . The trip point is now centered at  $1.4 \text{ V}$ .

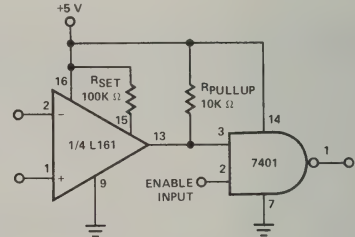


Zero Crossing Detector  
Figure 6



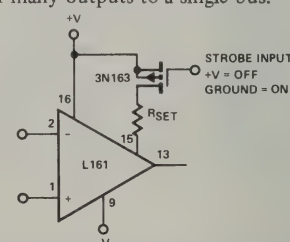
CMOS Line Receiver  
Figure 7

Mating the L161 with CMOS logic is natural since the L161 draws microamps from a single  $5 \text{ V}$  supply. However, the L161 will also drive TTL when a suitable pull-up resistor is provided. Figure 8 shows this combination. Total power drain of the circuit is much heavier due to the presence of the 7402. Propagation delays through the circuit are about  $1 \mu\text{sec}$ .



Driving TTL  
Figure 8

In many situations further power savings can be achieved by reducing or eliminating  $I_{SET}$  during part of the operating time. This is desirable, for example, when a system is multiplexed at a low duty cycle. The L161 may be strobed off completely by reducing  $I_{SET}$  to zero as shown in Figure 9. The 3N163 P-channel MOSFET is OFF when the strobe input is high so no set current flows into the L161. For a low strobe input, the 3N163 turns ON, pulling  $R_{SET}$  to the positive supply and turning on the comparator. The drain-source resistance of the 3N163 ( $3000 \Omega$ ) is negligible compared to  $R_{SET}$ . If the negative supply terminal of the L161 is returned to ground, the 3N163 may be eliminated and  $R_{SET}$  connected directly to the output of a CMOS gate. The L161 will now be ON when the CMOS output is high. When the L161 is strobed OFF, its outputs assume a high-impedance state; this "three state" operation facilitates the connection of many outputs to a single bus.

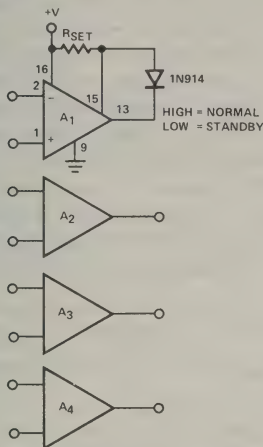


Strobing the L161 ON and OFF  
Figure 9



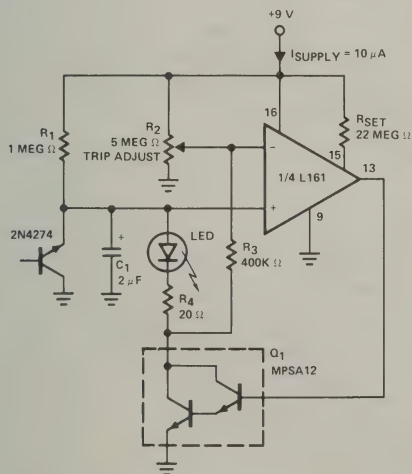
The L161 will switch itself into a standby mode if one of its outputs is connected to the  $I_{SET}$  terminal as illustrated in Figure 10. The diode blocks current when the output of  $A_1$  is HIGH, and operation of the other three comparators is normal. When the output goes low, however, the 1N914 conducts most of  $I_{SET}$  to the negative supply.  $I_{OL}$  is therefore nearly equal to  $I_{RSET}$ , and (from Equations 2 and 4),

$$I_{SUPPLY} = 21 I_{SET(actual)} = \frac{21 I_{OL}}{2B} = \frac{I_{RSET}}{10} \quad (5)$$



Switching the L161 to a Low Current  
"Standby" Mode  
Figure 10

if a  $\beta$  of 105 is assumed. Equation 5 states that the supply current of the L161 is reduced from  $21 \times I_{R1}$  (normal operation) to  $I_{R1}/10$ , a factor of 210 (or twice whatever  $\beta$  of  $Q_7$  is). Total supply drain is simply the current through  $R_{SET}$ . This circuit has an important advantage over the previous strobe circuit — even though the L161 is operating at a greatly reduced supply current, it is still ON and continues to function. If a lesser reduction in supply current is desired, connect a resistor in series with the diode.

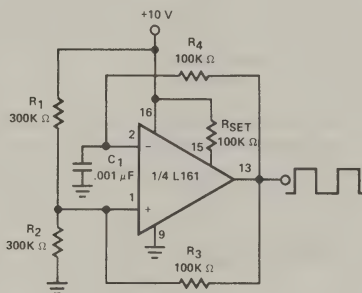


A Low Battery Indicator  
Figure 11

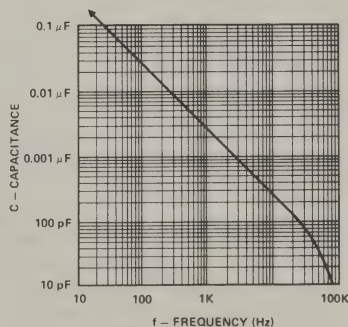
Figure 11 shows an L161 low battery indicator which flashes an LED when the battery voltage drops below a certain threshold. The 2N4274 emitter-base junction serves as a zener which establishes about 6 V on the L161's positive input. As the battery dies, the voltage at the negative input drops more quickly; when the low battery threshold (typically 7.5 V) is reached, the L161 output goes HIGH. This turns on the Darlington, which discharges  $C_1$  through the LED. The interval between flashes is roughly equal to  $R_1 C_1$ , which in this case is 2 seconds. By flashing the LED at a very low duty cycle, this circuit gives a low battery warning with only 10  $\mu A$  average power drain.

### Waveform Generators

Figure 12 is a square wave generator which is operable to over 100 kHz while Figure 13 depicts the typical frequency vs capacitance performance of the circuit. The low frequency limit is determined only by the size of  $C_1$ . Frequency is constant for supply voltages down to +5 V; below that the charging rate of  $C_1$  in the positive direction is determined by  $I_{OH}$  and not  $R_4$ . For lower voltage operation, increase  $R_4$  (and lower C accordingly) or decrease  $R_{SET}$ .



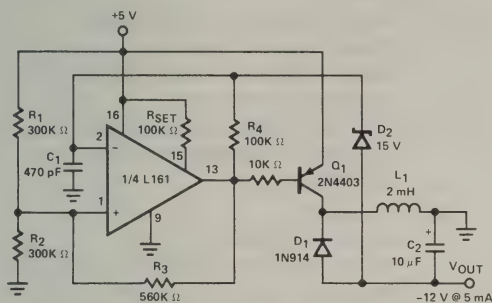
Squarewave Oscillator  
Figure 12



Frequency vs the Value of  $C_1$   
for the Squarewave Oscillator  
Figure 13



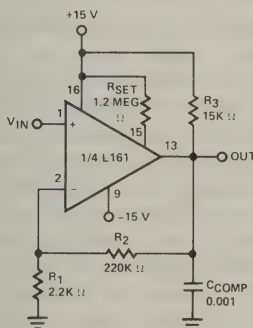
Figure 17 is a low power D.C. to D.C. converter obtained by adding a flyback circuit to the square wave oscillator. Operating frequency is 20 kHz to minimize the size of  $L_1$  and  $C_2$ . Regulation is achieved by zener diode  $D_2$ ; when the output is less than  $-12$  V, the zener breaks down and discharges  $C_1$  slightly which reduces the duty cycle of the oscillator below 50%. Maximum current available before the converter drops out of regulation is 5.5 mA at an overall efficiency of 71%. With no load the converter draws 590  $\mu$ A.



A Regulated DC to DC Converter  
Figure 17

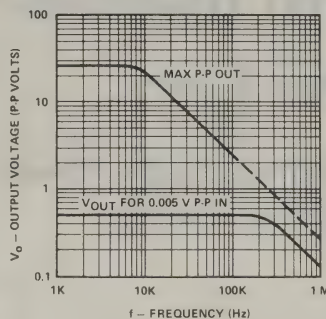
### Operational Amplifiers

While designed primarily as a comparator, the L161 will perform as an op amp if proper compensation is applied. Figure 18 is a simple gain of 100 amplifier with a gain-bandwidth product of 20 MHz! The primary limitation in the



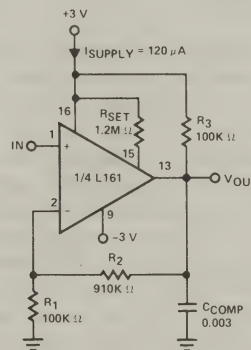
The L161 as a X100 Operational Amplifier  
Figure 18

performance is the low slew rate ( $0.3$  V/ $\mu$ sec) imposed by  $I_{OH}$  charging  $C_{COMP}$ . The effects of slew rate and compensation are shown in Figure 19. A lower gain amplifier



Frequency Response and Maximum Output  
for the X100 Op Amp  
Figure 19

requires a larger  $C_{comp}$ , which in turn further reduces slew rate. For this reason it may actually be advantageous in certain cases to lower the gain by placing a resistive divider at the input rather than raising  $R_1$ . Figure 20 shows a 700  $\mu$ watt X10 op amp whose slew rate is  $0.02$  V/ $\mu$ sec and is 3 dB down at 100 kHz.



A Micropower X10 Op Amp  
Figure 20



# Regulating Pulse Width Modulators

*designed for . . .*

## ■ Switched Mode Power Supplies (SMPS)

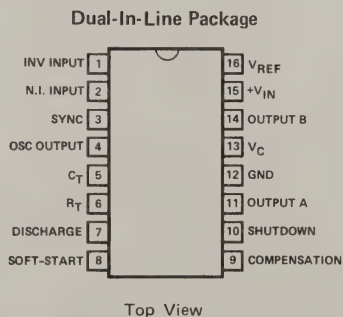
### BENEFITS

- Direct Pin for Pin Replacement for SG1525A/1527A
- Improved Performance Over SG1525A/1527A
  - Greatly Reduced Crossover Current Through Output Transistors
  - Greatly Reduced Transients With Separated Ground System
  - Fully Operational Up to 200 kHz Oscillator Frequency and a Typical 10% Pulse Width
- Wide Versatility
  - 8 to 35 Volt Operation
  - 100 Hz to 500 kHz Oscillator Range
  - Separate Oscillator Sync Terminal
  - Adjustable Deadtime Control
  - Internal Soft-Start
  - Input Undervoltage Lockout
  - Latching PWM to Prevent Multiple Pulses
- Lower Overall Parts Count
  - 5.1 Volt Onboard Reference Trimmed to  $\pm 1\%$
  - Dual 100 mA Source/Sink Output Drivers

### DESCRIPTION

The Si1525B/1527B series of pulse width modulator integrated circuits are designed to offer improved performance and lowered external parts count when used to implement all types of switching power supplies. In addition to being a direct replacement for the SG1525A/1527A the Si1525B/1527B features low crossover current through the output transistors and full operation up to 200 kHz while maintaining a typical 10% pulse width. The on-chip +5.1 volt reference is trimmed to  $\pm 1\%$  initial accuracy and the input common-mode range of the error amplifier includes the reference voltage, eliminating external potentiometers and divider resistors. A Sync input to the oscillator allows multiple units to be slaved together, or a single unit to be synchronized to an external system clock. A single resistor between the  $C_T$  pin and the Discharge pin provides a wide range of deadtime adjustment. These devices also feature built-in soft-start circuitry with only a timing capacitor required externally. A Shutdown pin controls both the soft-start circuitry and the output stages, providing instantaneous turn-off with soft-start recycle for slow turn-on. These functions are also controlled by an undervoltage lockout which keeps the outputs off and the soft-start capacitor discharged for input voltages less than that required for normal operation. Another unique feature of these PWM circuits is a latch following the comparator. Once a PWM pulse has been terminated for any reason, the outputs will remain off for the duration of the period. The latch is reset with each clock pulse. The output stages are totem-pole designs capable of sourcing or sinking 100 mA. The Si1525B output stage features NOR logic, giving a LOW output for an OFF state. The Si1527B utilizes OR logic which results in a HIGH output level when OFF.

### PIN CONFIGURATION



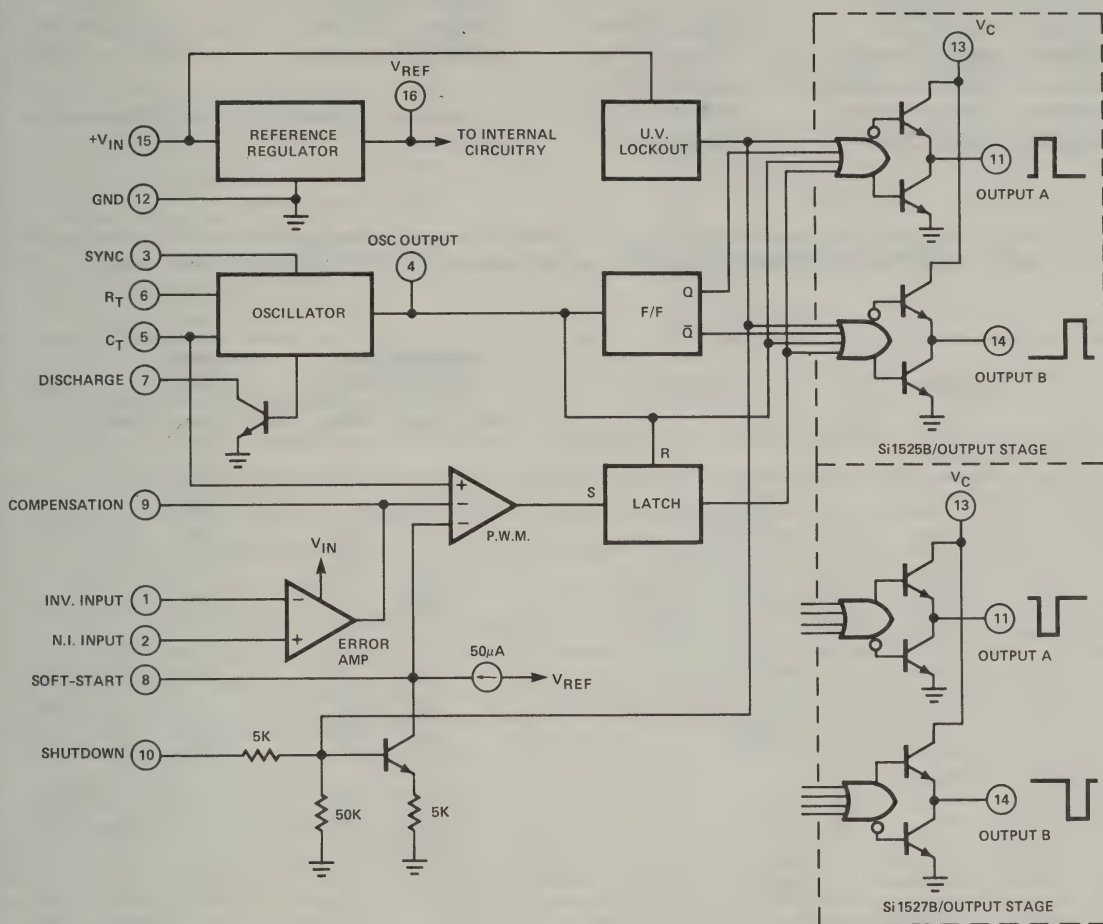
#### ORDER NUMBERS:

Si1525BK	Si1527BK
Si2525BK	Si2527BK
Si3525BK	Si3527BK

See Package 10



# BLOCK DIAGRAM



## ABSOLUTE MAXIMUM RATINGS\* ( $T_A = 25^\circ\text{C}$ unless noted otherwise)

Supply Voltage ( $+V_{IN}$ ) . . . . . +40V  
 Collector Supply Voltage ( $V_C$ ) . . . . . +40V  
 Logic Inputs . . . . .  $-0.3\text{V}$  to  $+5.5\text{V}$   
 Analog Inputs . . . . .  $-0.3\text{V}$  to  $+V_{IN}$   
 Output Current, Source or Sink . . . . . 200 mA  
 Reference Output Current . . . . . 50 mA  
 Oscillator Charging Current . . . . . 5 mA  
 Power Dissipation at  $T_A = +25^\circ\text{C}$ \*\* . . . . . 1000 mW  
 Thermal Resistance: junction  
 to ambient . . . . .  $100^\circ\text{C/W}$

Power Dissipation at  $T_C = +25^\circ\text{C}$ \*\*\* . . . . . 2000 mW  
 Thermal Resistance: junction to case . . . . .  $60^\circ\text{C/W}$   
 Operating Junction Temperature . . . . .  $+150^\circ\text{C}$   
 Storage Temperature Range . . . . .  $-65^\circ\text{C}$  to  $+150^\circ\text{C}$   
 Lead Temperature  
 (Soldering, 10 seconds) . . . . .  $+300^\circ\text{C}$

\*Values beyond which damage may occur.

\*\*Derate at  $10\text{ mW}/^\circ\text{C}$  for ambient temperatures above  $+50^\circ\text{C}$ .

\*\*\*Derate at  $16\text{ mW}/^\circ\text{C}$  for case temperatures above  $+25^\circ\text{C}$ .

Si1525B Si1527B Si2525B Si2527B Si3525B Si3527B

6

Linear

## RECOMMENDED OPERATING CONDITIONS 1

Input Voltage ( $+V_{IN}$ ) . . . . . +8V to +35V  
 Collector Supply Voltage ( $V_C$ ) . . . +4.5V to +35V  
 Sink/Source Load Current  
 (each output) . . . . . 0 to 100 mA  
 Reference Load Current . . . . . 0 to 20 mA  
 Oscillator Frequency Range . .100 Hz to 500 kHz  
 Oscillator Timing Resistor . . . . 2k $\Omega$  to 150k $\Omega$   
 Oscillator Timing Capacitor . . .001  $\mu$ F to 0.1  $\mu$ F

Deadtime Resistor Range . . . . . 0 to 500 $\Omega$   
 Operating Ambient Temperature Range  
 Si3525B, Si3527B . . . . . 0°C to +70°C  
 Si2525B, Si2527B . . . . . -25°C to +85°C  
 Si1525B, Si1527B . . . . . -55°C to +125°C

<sup>1</sup> Range over which the device is functional and parameter limits are guaranteed.

ELECTRICAL CHARACTERISTICS ( $+V_{IN} = 20V$ , and over operating temperature, unless otherwise noted)

Parameter		Conditions	SI1525B/2525B SI1527B/2527B			SI3525B SI3527B			Units
			Min	Typ	Max	Min	Typ	Max	
Reference Section									
1	Output Voltage	T <sub>j</sub> = 25°C	5.05	5.10	5.15	5.00	5.10	5.20	V
2	Line Regulation	V <sub>IN</sub> = 8 to 35V		10	20		10	20	mV
3	Load Regulation	I <sub>L</sub> = 0 to 20 mA		20	50		20	50	mV
4	Temperature Stability <sup>2</sup>	Over Operating Range		20	50		20	50	mV
5	Total Output Variation <sup>2</sup>	Line, Load, and Temp	5.00		5.20	4.95		5.25	V
6	Short Circuit Current	V <sub>REF</sub> = 0, T <sub>j</sub> = 25°C		80	100		80	100	mA
7	Output Noise Voltage <sup>2</sup>	10 Hz ≤ f ≤ 10 kHz, T <sub>j</sub> = 25°C		40	200		40	200	μVrms
8	Long Term Stability <sup>2</sup>	T <sub>j</sub> = 125°C		20	50		20	50	mV/khr
Oscillator Section <sup>3</sup>									
9	Initial Accuracy <sup>2,3</sup>	T <sub>j</sub> = 25°C		±2	±6		±2	±6	%
10	Voltage Stability <sup>2,3</sup>	V <sub>IN</sub> = 8 to 35V		±0.3	±1		±1	±2	%
11	Temperature Stability <sup>2</sup>	Over Operating Range		±3	±6		±3	±6	%
12	Minimum Frequency	R <sub>T</sub> = 150 kΩ, C <sub>T</sub> = 0.1 μF			100			100	Hz
13	Maximum Frequency	R <sub>T</sub> = 2 kΩ, C <sub>T</sub> = 1 nF	400			400			kHz
14	Current Mirror	I <sub>RT</sub> = 2 mA	1.7	2.0	2.2	1.7	2.0	2.2	mA
15	Clock Amplitude <sup>2,3</sup>		3.0	3.5		3.0	3.5		V
16	Clock Width <sup>2,3</sup>	T <sub>j</sub> = 25°C	0.3	0.5	1.0	0.3	0.5	1.0	μsec
17	Sync Threshold		1.2	2.0	2.8	1.2	2.0	2.8	V
18	Sync Input Current	Sync Voltage = 3.5V		1.0	2.5		1.0	2.5	mA

<sup>2</sup> These parameters, although guaranteed over the recommended operating conditions, are not 100% tested in production.

<sup>3</sup> Tested at  $f_{OSC} = 40$  kHz ( $R_T = 3.6$  k $\Omega$ ,  $C_T = .01$   $\mu$ F,  $R_D = 0\Omega$ ).

CMCD

**TENTATIVE DATA SHEET.** This page provides tentative information on a new product. Siliconix reserves the right to change specifications for this product in any manner without notice.

## ELECTRICAL CHARACTERISTICS (CONT)

Parameter		Conditions	Si1525B/2525B Si1527B/2527B			Si3525B Si3527B			Units
			Min	Typ	Max	Min	Typ	Max	
Error Amplifier Section (V <sub>CM</sub> = 5.1 Volts)									
19	Input Offset Voltage			0.5	5		2	10	mV
20	Input Bias Current			1	10		1	10	μA
21	Input Offset Current				1			1	μA
22	DC Open Loop Gain	R <sub>L</sub> ≥ 10 MegΩ	60	75		60	75		dB
23	Gain-Bandwidth Product <sup>4</sup>	A <sub>V</sub> = 0 dB, T <sub>j</sub> = 25°C	1	2		1	2		MHz
24	Output Low Level			0.2	0.5		0.2	0.5	V
25	Output High Level		3.8	5.6		3.8	5.6		V
26	Common Mode Rejection	V <sub>CM</sub> = 1.5 to 5.2V	60	75		60	75		dB
27	Supply Voltage Rejection	V <sub>IN</sub> = 8 to 35V	50	60		50	60		dB
P.W.M. Comparator									
28	Minimum Duty Cycle				0			0	%
29	Maximum Duty Cycle		45	49		45	49		%
30	Input Threshold <sup>5</sup>	Zero Duty Cycle	0.6	0.9		0.6	0.9		V
31	Input Threshold <sup>5</sup>	Max Duty Cycle		3.3	3.6		3.3	3.6	V
32	Input Bias Current <sup>4</sup>			.05	1.0		.05	1.0	μA
Soft-Start Section									
33	Soft Start Current	V <sub>SHUTDOWN</sub> = 0V	25	50	80	25	50	80	μA
34	Soft Start Voltage	V <sub>SHUTDOWN</sub> = 2V		0.4	0.6		0.4	0.6	V
35	Shutdown Input Current	V <sub>SHUTDOWN</sub> = 2.5V		0.4	1.0		0.4	1.0	mA
Output Drivers (Each Output) (V <sub>C</sub> = 20 Volts)									
36	Output Low Level	I <sub>SINK</sub> = 20 mA		0.2	0.4		0.2	0.4	V
37		I <sub>SINK</sub> = 100 mA		1.0	2.0		1.0	2.0	V
38	Output High Level	I <sub>SOURCE</sub> = 20 mA	18	19		18	19		V
39		I <sub>SOURCE</sub> = 100 mA	17	18		17	18		V
40	Undervoltage Lockout	V <sub>Comp</sub> and V <sub>SS</sub> = high	6	7	8	6	7	8	V
41	Collector Leakage <sup>6</sup>	V <sub>C</sub> = 35V			200			200	μA
42	Rise Time <sup>4</sup>	C <sub>L</sub> = 1 nF, T <sub>j</sub> = 25°C		100	600		100	600	nsec
43	Fall Time <sup>4</sup>	C <sub>L</sub> = 1 nF, T <sub>j</sub> = 25°C		50	300		50	300	nsec
44	Shutdown Delay <sup>4</sup>	V <sub>SH</sub> = 3V, C <sub>S</sub> = 0, T <sub>j</sub> = 25°C		0.2	0.5		0.2	0.5	μsec
Total Standby Current									
45	Supply Current	V <sub>IN</sub> = 35V		14	20		14	20	mA

CMCD

<sup>4</sup> These parameters, although guaranteed over the recommended operating conditions, are not 100% tested in production.<sup>5</sup> Tested at  $f_{OSC} = 40$  kHz ( $R_T = 3.6$  k $\Omega$ ,  $C_T = .01$   $\mu$ F,  $R_D = 0$   $\Omega$ ).<sup>6</sup> Applies to Si1525B/2525B/3525B only, due to polarity of output pulses.

**TENTATIVE DATA SHEET.** This page provides tentative information on a new product. Siliconix reserves the right to change specifications for this product in any manner without notice.

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# Introduction to Quantized Feedback

## INTRODUCTION

Siliconix' "Quantized Feedback" (or charge balancing as it is sometimes called) approach towards A/D conversion is an integrating technique, implemented through the use of an analog processor and digital controller. Intrinsic features of this approach are Auto-Polarity, Auto-Zero and ratio-metric operation. As we shall see, this technique offers superior linearity, normal mode rejection and stability over that of other integrating techniques while at the same time requiring no critical components except a stable voltage reference.

Let's begin our discussion by considering the following op-amp adder:

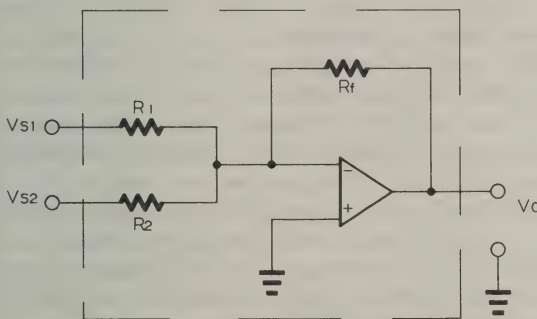


Figure 1.

$$\text{where } V_0 = -\left(\frac{R_f V_{S1}}{R_1} + \frac{R_f V_{S2}}{R_2}\right)$$

Recalling basic op-amp operation, it is easy to see that the output voltage  $V_0$  is equal to the algebraic sum of  $V_{S1}$  and  $V_{S2}$  appropriately scaled. By taking this simple adder circuit and a few

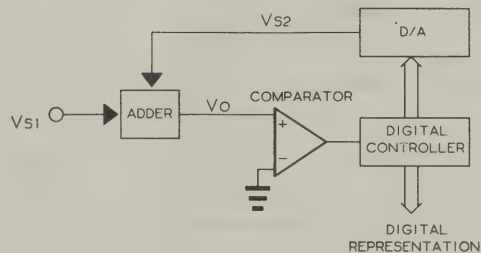


Figure 2.

Rudimentary A/D Converter

$$\frac{V_{S1}}{R_1} \approx -\frac{V_{S2}}{R_2} \therefore V_0 \approx 0$$

$V_{S1}$  must be stable during conversion  $\therefore$  requires S/H in front end.

additional components it is possible to construct a rudimentary A/D converter as shown in Figure 2.

If  $V_{S1}$  is the unknown voltage that we would like to measure and  $V_{S2}$  an input voltage that we control, then by examining the state of  $V_0$  and feeding back a  $V_{S2}$  sufficient to cancel out  $V_{S1}$ , (i.e. keep  $V_0$  as close to zero as possible) we can digitally keep track of  $V_{S1}$  as diagrammed in Figure 2.

This is the technique used by successive approximation and counting type converters. Although conceptually simple and apparently easily implemented, this technique is entirely dependent upon the linearity and stability of the feedback D/A. In addition, the complexity of a very high precision D/A (greater than 8 bits input) which would be necessary to construct a high-precision A/D could prove prohibitive both in cost and circuit complexity. A more accurate and less complex approach as we shall see, would be to feed back just 2 voltage levels (say  $+V_{\text{ref1}}$ ,  $-V_{\text{ref2}}$ ) instead of the multitude of voltages possible with a D/A. However in using this approach we become interested in the time average of the feedback voltage as compared to the voltage under measurement, since we are now restricted to 2 voltage levels which should bracket the input voltage to be measured.

This being the case we now want to change our simple op-amp adder (of Fig. 1) into an integrator (Fig. 3) to perform the necessary averaging function.

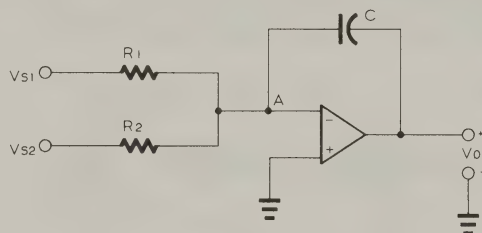


Figure 3.  
Op-Amp Integrator

$$\text{where } V_0 = -1/C \int \left( \frac{V_{S1}}{R_1} + \frac{V_{S2}}{R_2} \right) dt$$

Once again  $V_{S1}$  is the unknown voltage we would like to measure and  $V_{S2}$  one of two voltage levels returning from our feedback network. We examine  $V_0$  and feed back a voltage ( $V_{S2}$ ) such that the time average of  $V_{S2}$  is sufficient to cancel out the analog unknown,  $V_{S1}$ . However since the input node (point A in Figure 3) to our analog adder is really a virtual ground, what we are really trying to balance out are the 2 currents flowing into the node (i.e.  $\frac{V_{S1}}{R_1}$  and  $\frac{V_{S2}}{R_2}$ ). This is easily seen in the integrator circuit (Fig. 3) where the quantity that

we are interested in integrating  $\left( \frac{V_{S1}}{R_1} + \frac{V_{S2}}{R_2} \right)$  is in

reality a current. But recalling that the integral of a current is charge,  $Q = \int i dt$ , what we are really trying to balance in order to keep  $V_0$  as close to zero as possible is the charge on the capacitor C as supplied by  $V_{S1}$  and  $V_{S2}$ . But since in our averaging process the feedback  $V_{S2}$  can only assume one of 2 voltage levels for an integer number of *time units*, we can only add or take away capacitor charge in quantum lumps  $\left( -1/C \frac{V_{\text{ref1}} dt}{R_2} \text{ or } +1/C \frac{V_{\text{ref2}} dt}{R_2} \right)$ , thus giving us our

technique name *quantized feedback*. A block diagram of such an A/D converter is shown in Figure 4.

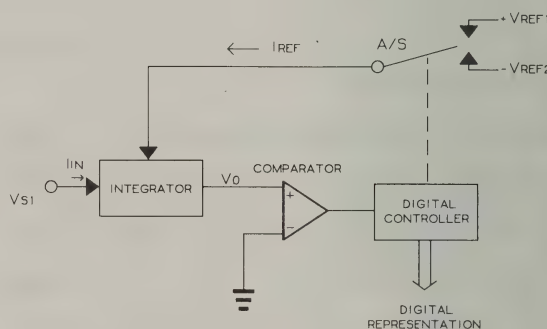


Figure 4.  
Quantized Feedback A/D Converter

Figure 4 is the quantized feedback technique in its most basic form. As previously mentioned, by feeding back only 2 voltage levels we can significantly improve our linearity and accuracy in high precision measurements while reducing our feedback circuit complexity to a switch and stable voltage reference. Although our digital control logic is now somewhat more complex as compared to a counting technique, we are able to effect significant gains in precision with only modest increases in digital control circuit complexity. And since in this technique both the unknown and reference voltages are simultaneously integrated with the objective of keeping the integrator output as close to zero as possible, large voltage swings at the integrator output as typically seen in Dual Slope converters are avoided, thus easing integrator requirements. This dynamic feedback measurement process also ensures equally spaced count transition windows under varying conversion rates; even

around zero. Although timing is now critical to proper high resolution operation, our task is easily met through dedicated digital-control logic. Another feature inherent in this technique is that since we are trying to balance charges which are proportional to the input voltages, scale changes are easily accomplished through simple ratiometric resistor ( $R_1$  and  $R_2$ ) changes (i.e. Fullscale  $\propto R_1/R_2$ ).

The basic principles underlying the quantized feedback technique should now be apparent, as well as the fundamental relationship between the voltage-under-measurement ( $V_{IN}$ , formerly  $V_{SI}$ ) and our 2 feedback voltage levels  $V_{ref1}$  and  $V_{ref2}$ . That is, the current supplied by  $V_{IN}$  must be of opposite polarity and lie within the range bounded by the reference currents,  $I_{ref2} \leq I_{in} \leq I_{ref1}$ , (see Fig. 4) in order for  $V_{IN}$  to be measured. So in order to measure a  $\pm V_{IN}$  using our simple system, we would have to supply both a  $\pm$  reference voltage. We are also limited in our simple system to

measuring single ended inputs (i.e. no common mode voltage). Siliconix however, has overcome these problems through an enhancement of the basic technique in which only 1 polarity  $V_{ref}$  is necessary for auto-polarity operation and where a zeroing measurement is automatically performed. Briefly, the way it is done is through the use of negative feedback to impress a system offset voltage when zeroing.

Let's now look at Figure 5 which is a diagram of the analog processor architecture as found in the Siliconix LD111A, LD120 and LD122 (the input buffer is user-supplied). Note that outside of a few additions, this circuit closely resembles our basic Quantized Feedback Converter (Figure 4). We still have the integrator summing node, pin 9 fed by a voltage reference source, unknown input voltage source, and (new here) an Auto-Zero (whose use will soon be explained) voltage source. The control logic near the Auto-Zero buffer is used by the digital controller to implement the

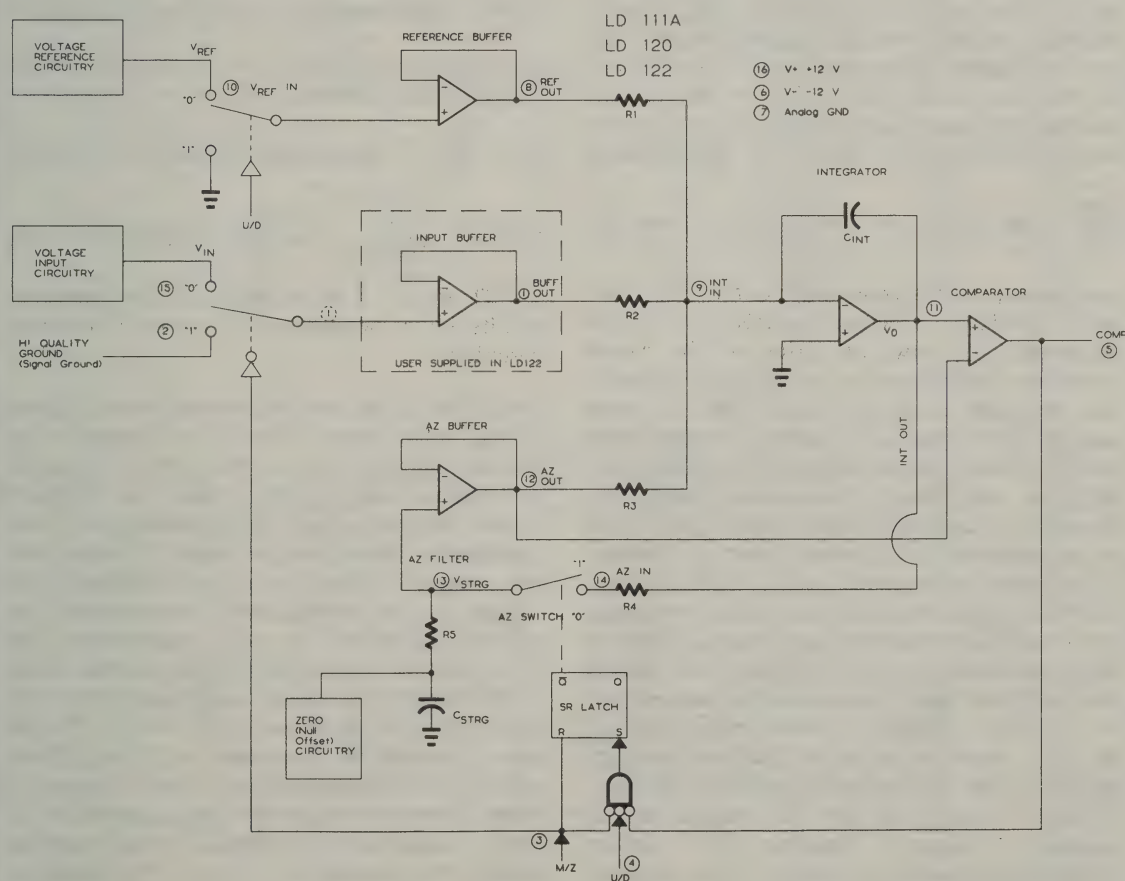


Figure 5. Siliconix Analog Processor



measurement algorithm. All of the inputs are now unity buffered so that loading effects on inputs are effectively eliminated. As before the output of the integrator is fed to a comparator whose output COMP 5 is monitored by the digital control logic. A feedback control signal UP/DOWN, U/D 4, from the digital controller determines which of 2 reference voltage levels ( $V_{ref}$  or GND) are to be fed back. The addition of the Measure/Zero M/Z 3 control line permits the division of our sampling process into 2 parts, a zeroing and a measuring interval.

The aforementioned system offset impression is accomplished in an auto-zeroing interval which is of sufficient duration to ensure equilibrium conditions. In the auto-zeroing interval the M/Z line is set low, connecting the input buffer to the input signal ground (or negative input if doing differential measurements). With the combination of the other 2 control lines U/D and COMP, the SR latch is set, forcing the switch between pins ⑬ and ⑭ closed. The digital control logic toggles the U/D line at a 50% duty cycle rate, thereby feeding a d-c pulse train (of amplitude  $V_{ref}$ ) to the reference buffer. Ignoring all other contributions to the sum node, the reference buffer will contribute a current equal to  $V_{ref}/R_1$  to the node half of the time with the average current being  $\frac{V_{ref}}{2R_1}$ . The output of the integrator feeds the

comparator, but the comparator output is ignored in the zeroing interval so that this route can be disregarded for now. By virtue of the closed Auto-Zero switch however, the integrator output is also fed back to the A/Z buffer which in turn supplies current to the integrator summing node thereby forming a closed negative feedback loop. Along the way though, the integrator output  $V_0$  charges up a capacitor CSTRG which, as we shall see, is instrumental to proper operation. Resistor  $R_4$  is used to guard against oscillations by assuring that the negative feedback gain is less than unity.  $R_5$  is used to provide low pass filtering action in conjunction with CSTRG. Now since our buffers have such high input impedances, let's assume that the voltage on CSTRG is the same as that on pin ⑬, the input to the A/Z buffer or  $V_{STRG}$ . Because of the filtering action provided by  $R_5$  - CSTRG,  $V_{STRG}$  will be the average of the integrator output. Therefore, a current  $V_{STRG}/R_3$ , opposite in polarity to that supplied by the reference buffer will be fed to the summing node. With a little imagination we can envision that

the DC or time average of all the currents flowing into the integrator sum node will eventually cancel each other out and in equilibrium the net current will equal zero. There will however, be an integrator output voltage  $V_0$  the average of which will be  $V_{STRG}$  and both will be opposite in polarity to the  $V_{ref}$  voltage. Thus far all mention of the input buffer and error/offset currents have been avoided, but it can easily be seen that any current supplied through the input buffer from the negative differential input (Hi-Quality Ground ②), as well as any error currents will simply either aid or oppose the A/Z buffer in its attempts to balance out current from the reference source. Consequently in equilibrium, the  $V_{STRG}$  will be shifted slightly from what it would have been had none of these other current sources been present. Of course we assume that these additional sources do not change appreciably with time when we later move into the measurement interval. The key point to remember here is that the reference buffer is constantly supplying an average current of  $1/2 \frac{V_{ref}}{R_1}$  to the integrator sum node and in auto-zero

equilibrium the sum of all other sources of current (A/Z, INPUT, ERROR) are equal and opposite to  $1/2 \left( \frac{V_{ref}}{R_1} \right)$ . This auto-zero equilibrium current balance  $\left( \frac{V_{ref}}{2R_1} \right)_{avg} - \frac{V_{STRG}}{R_3}$  (supplied by A/Z,

INPUT, etc.) = 0 is our desired offset impression and its use in the measurement process will now be described.

One of the things that we have succeeded in doing in the auto-zeroing process is to determine the average integrator output voltage level ( $V_{STRG}$  or A/Z output buffer voltage) when our system is zeroed. By tracing back the negative input of the comparator, we can see that this is the voltage that our integrator output is compared against when we actually do our measurements. When we leave the auto-zeroing interval to do a measurement, the M/Z line goes high, reconnecting the input buffer to the + end of the voltage under measurement and opening the switch between ⑬ and ⑭. We can now appreciate the importance of CSTRG, for in addition to averaging out the integrator output, it holds for us the value of  $V_{STRG}$  necessary for proper comparator operation and charge balancing. During the measurement interval  $V_{IN}$  begins to supply current to the sum node and the comparator output is closely monitored by the



digital controller. In response to the state of COMP, the controller feeds back either  $V_{ref}$  or GND to the reference buffer by toggling the U/D line. Measurement now is exactly as described in our simple A/D converter circuit (Figs. 3 & 4). However since all of our equilibrium conditions in auto-zero were calculated with an average  $\frac{V_{ref}}{2}$

being fed into the reference buffer, feeding back a constant  $V_{ref}$  will result in a net current over and above that in equilibrium of  $+V_{ref}/2R_1$  being sent to the sum node. Likewise feeding back a constant GND will cause a net current of  $-V_{ref}/2R_1$  (from A/Z, etc.) to flow into the sum node. So whatever polarity  $V_{IN}$  may be, we will be able to balance it out with appropriate resistor scaling. An interesting

aside here is that in all of our discussions the absolute polarity of  $V_{ref}$  (i.e. + or - with respect to GND) was never specified and any polarity could have been used with equal, but differing polarity results. However due to the nature of the switch Siliconix uses with the  $V_{ref}$  buffer (PMOS) only positive references will work.

## THE "QUANTIZED FEEDBACK" ALGORITHM

The measurement algorithm used by all of our digital processor chips (LD110, 114, 121A) is basically the same. There are some minor variations due to slightly different analog control structures and the different precision that each

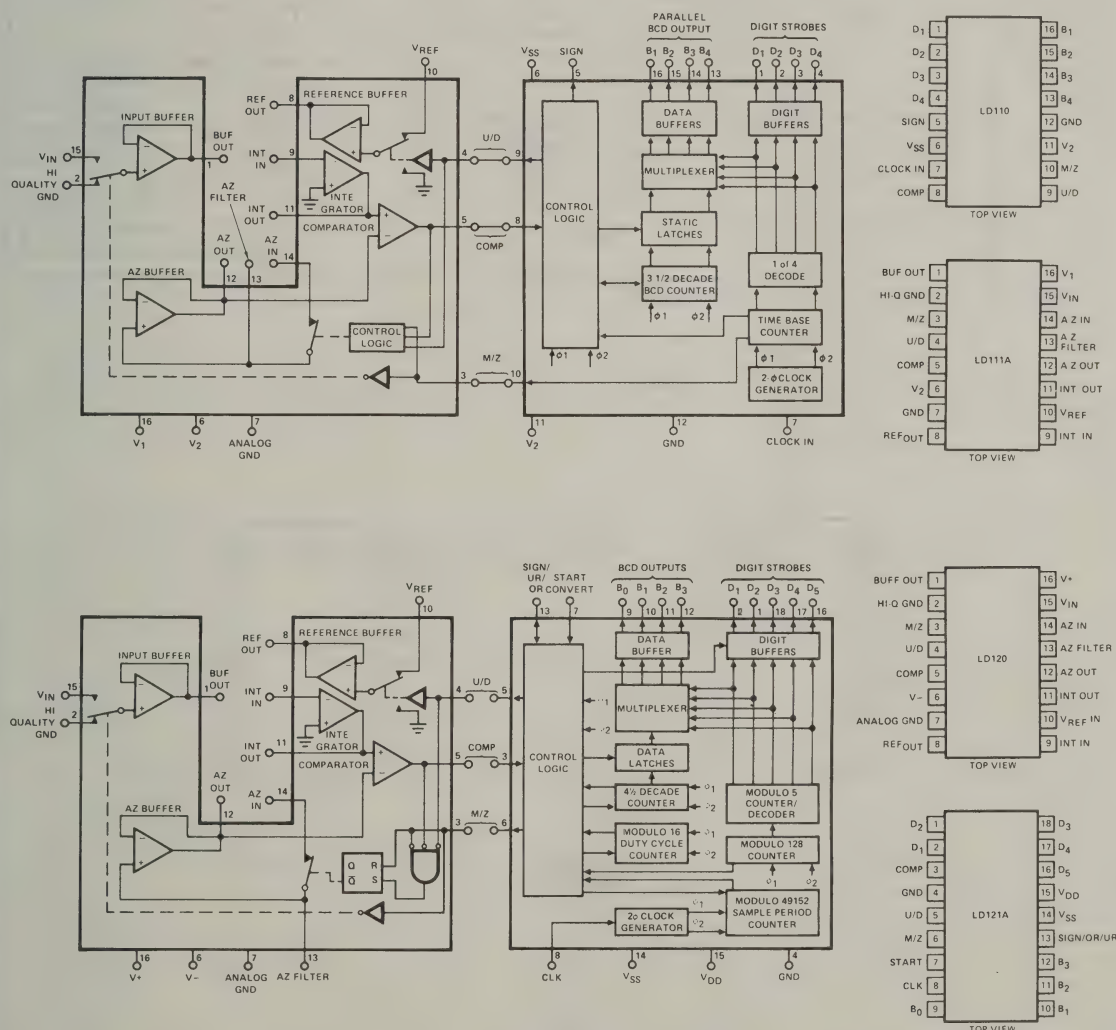


Figure 6

processor offers. For an example, the LD110 (114),  $3\frac{1}{2}$  digits and the LD121A,  $4\frac{1}{2}$  digits. The LD114 is the same as the LD110, but with additional digital functions pinned out. All chips, though for greater stability and accuracy derive their timing from a stable clock signal generated either internally or externally. Inside the chip

the clock is further divided by 2, or split into a 2-phase signal as the case may be. However, for our discussion, the timing signal as used by all of the internal circuitry will be the clock. Figure 6 shows the internal organization, pinout and typical analog processor interfacing for each of the digital controllers.

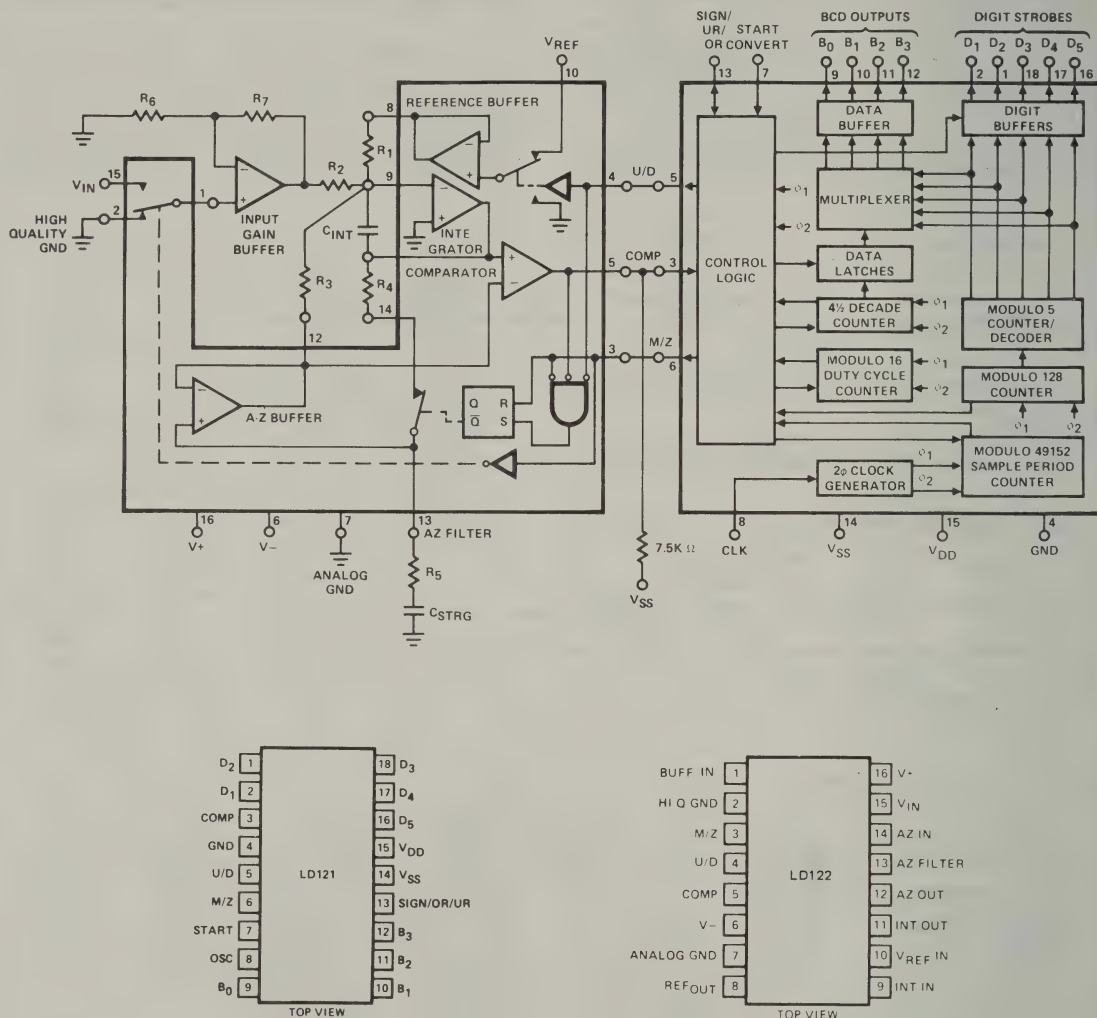


Figure 6  
Continued

Every sampling interval is composed of an integral number of clock periods ( $LD110 = 6144$ ,  $LD121A = 49,152$ ). The sampling interval can be further subdivided into 2 operational periods, the Auto-Zero (A/Z) and Measure intervals. The A/Z interval, as we know, gives us a means of nulling offset voltages and establishing a second tracking reference voltage necessary for bipolar conversion. The interval is signified by the Measure-Zero control line (M/Z) going low and consists of the following number of clocks:  $LD110 = 2048$ ,  $LD121A = 16,384$ . In the Measurement interval (when  $M/Z = 1$ ), the actual charge balancing process is implemented and consists of the following number of clocks:  $LD110 = 4096$ ,  $LD121A = 32,768$ . As you may have noticed, A/Z makes up  $1/3$  and Measure Interval  $2/3$ 's of the sampling interval. The reason why such a significant fraction of time is devoted

to A/D to insure that equilibrium zero conditions are attained. The M/Z line is the principal signal to the analog circuitry to tell it which interval it is in so that the appropriate switches can be closed. The Up-Down (U/D) line, on the other hand, is responsible for controlling the reference voltage fed back in the A/Z and Measure Intervals. As we may recall, during the A/Z interval a 50% duty cycle pulse train of  $V_{REF}$  amplitude is fed back in the analog system. This is accomplished by toggling the U/D line once every 4 clocks in the  $LD110$  and once every 8 clocks in the  $LD121A$ .

Figure 7 shows typical waveforms in the auto-zero interval for the  $LD110$ . The  $LD121A$  has essentially the same timing except that twice as many clocks are required for U/D toggling.

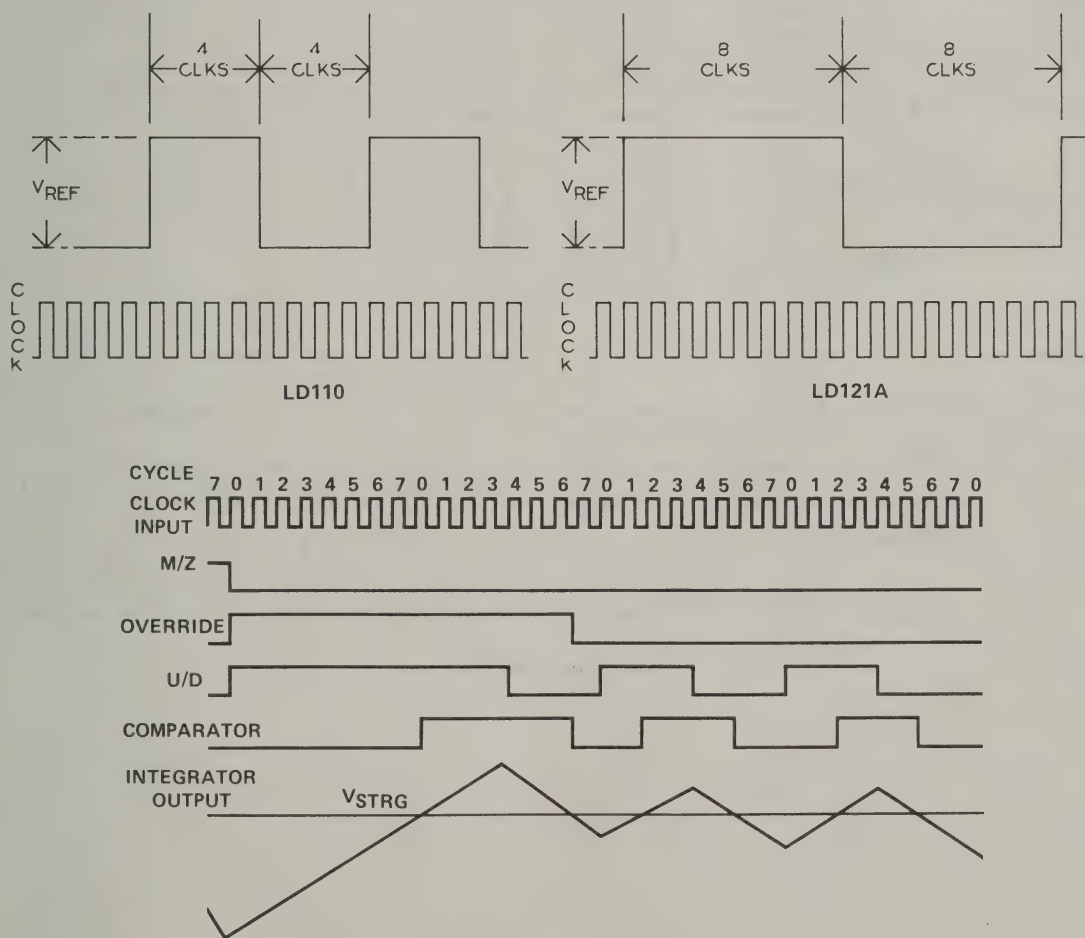
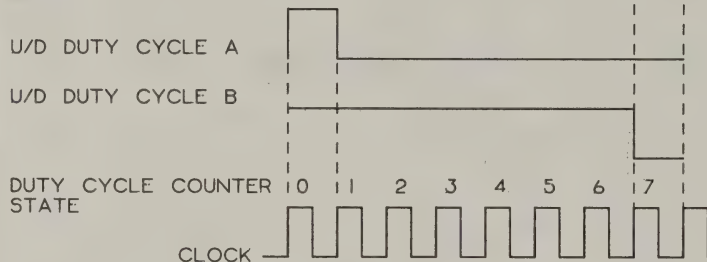


Figure 7  
Auto-Zero Timing

In the measure interval, where we attempt to balance integrator charge, U/D is set in response to the state of the COMP input, so that the appropriate reference voltage will be fed back in the analog system. A counter automatically increments or decrements once every clock cycle, depending on the state of the U/D line, so that an accurate record can be kept of the net number of charge packets fed back. Ordinarily one would think that once every clock cycle the U/D would be set accordingly. However, since this technique is as dependent on timing as it is on feedback voltage level, we really have to be mindful of U/D

transitions since they bring with them error in the form of rise and fall time. One way around this problem is to insure that in every measure interval there is always the same number of U/D transitions, irrespective of the unknown,  $V_{IN}$ . This can be done by dividing the measure interval into an integral number of duty cycle periods in which the U/D line can assume 1 of 2 duty cycle waveforms. In the LD121A the duty cycle period consists of 16 clocks while it's 8 in the LD110. The 2 duty cycle waveforms possible in each 16 or 8 clock period is:

#### LD110



#### LD121A

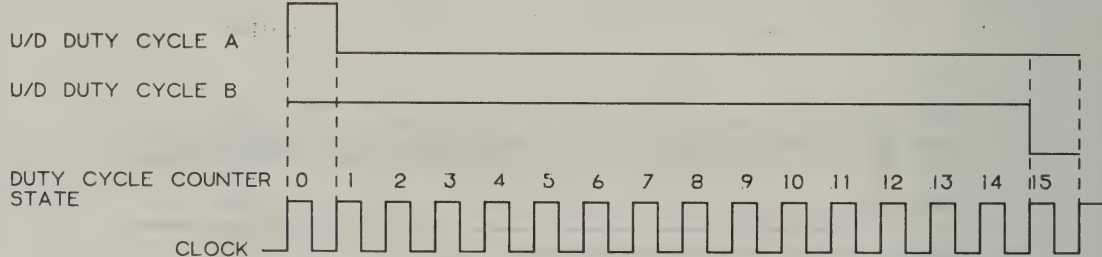


Figure 8 Duty Cycle Waveforms



So instead of depositing a maximum possible ( $\pm 16$  or  $\pm 8$ ) charge packets every duty cycle period, we have to be content with a net maximum of  $\pm 14$  or  $\pm 6$ . Consequently the maximum counts possible are: LD110 = 3072, LD121A = 28,672. However, since these maximum counts are larger than the advertised precision of the A/D's, overrange capability is possible and built into some of the converters.

Since we can only feedback rather large lumps of charge ( $\pm 14$ ,  $\pm 6$  counts), when the measure interval comes to an end, there will, undoubtedly, be some residual charge left over to be resolved to the nearest count. This is done in a brief override period at the start of the A/Z interval where normal A/Z operation is temporarily inhibited while we fine tune (i.e. abandon duty cycles and feedback charge packets one at a time). The override period starts at the end of the measure interval when M/Z  $\rightarrow$  low and the input buffer is switched to input 'gnd' so that no more charge is accumulated. The U/D line is set high and held until the comparator goes high and the next state 8 of the duty cycle counter comes around at which time U/D is set low. When the comparator next goes low again, the override period is ended (M/Z = 0, COMP = 0, U/D = 0, Auto-Zero switch closes initiating normal Auto-Zero action). The counter which until now has been faithfully keeping track of the charge packets fed back, is inhibited and its count used to update the data outputting latches on the next clock pulse. Figure 9 shows typical Measure, Override, and Auto-Zero waveforms in an LD120/LD121A system.

Now that the measurement algorithm has been described, a few words about the relationship

between the count and unknown input voltage are in order. What the count represents is the net number of reference charge units ( $\pm \frac{V_{REF}}{2R_1} \frac{1}{f_{CLK}}$ ) which were needed to cancel out the charge as supplied by the unknown input

$$\left( \frac{V_{IN}}{R_2} \cdot \frac{\# \text{ clocks in measure interval}}{f_{CLK}} \right).$$

Neglecting signs, this equality is:

$$\text{COUNT} \cdot \frac{V_{REF}}{2R_1} \cdot \frac{1}{f_{CLK}} =$$

$$\frac{V_{IN}}{R_2} \cdot \frac{\# \text{ clocks in measure interval}}{f_{CLK}}$$

rearranging, this becomes:

$$\text{COUNT} = \frac{V_{IN}}{V_{REF}} \cdot \frac{R_1}{R_2} \cdot 2$$

(# clocks in measure interval).

For an LD121A with 32,768 clocks in the measure interval, this equality becomes:

$$\text{COUNT} = \frac{V_{IN}}{V_{REF}} \cdot \frac{R_1}{R_2} \cdot 65,536$$

By manipulating the resistor ratios and  $V_{REF}$  we could theoretically scale the A/D to any input voltage range desired. Practical circuit limitations, though, prevent us from getting carried away.

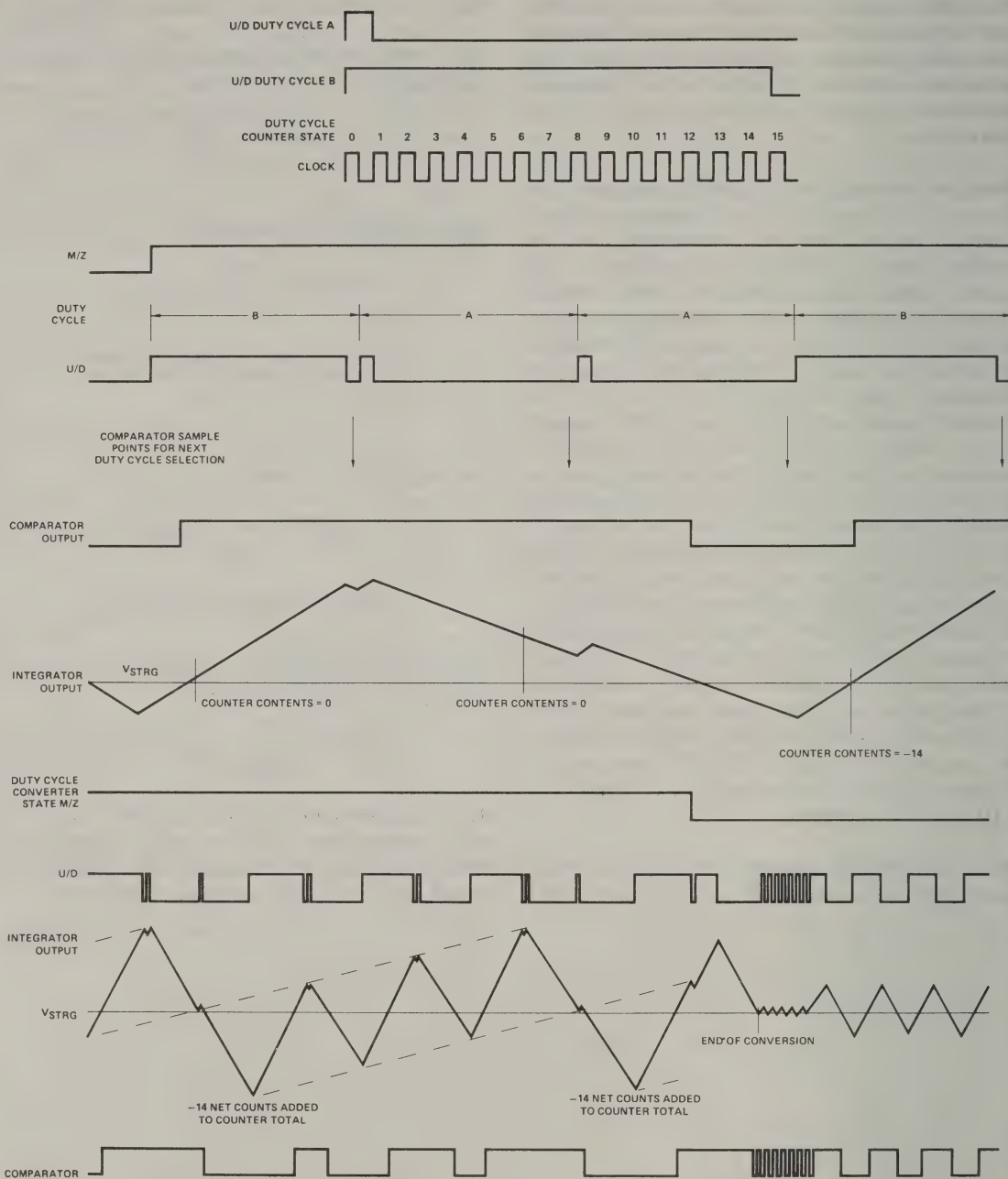


Figure 9. Up/Down and Integrator Waveforms

# Microprocessor Interface Techniques As Applied to the Siliconix A/D Converter Family

## INTRODUCTION

When attempting to interface a microprocessor system with a peripheral device (in this case an A/D) that operates at a substantially slower speed, the communications process between the system and peripheral can be thought of as lying between two extremes, synchronous and asynchronous operation. Either mode of operation will offer trade-offs between speed or throughput, and hardware complexity. For instance, in a synchronous communications approach, overall system speed is effectively reduced to that of the slow peripheral as the system must wait for a response or handshake from it. In an asynchronous approach however, both the system and the peripheral are able to operate at their own respective clock rates, with the speed differential problem being solved through the use of an interface buffer between the two. Hardware complexity is considerably higher here though than in a handshaking synchronous interface because such an asynchronous buffer is usually implemented through the use of latches to retain all of the data.

More often than not in A/D application notes or data sheets where an interface to a microprocessor is shown, the ap-

proach taken is the use of a peripheral interface chip such as an 8255 PPI or a 6820 PIA. While this approach will ultimately get the job done, it's extremely costly in terms of all of the negative features of both asynchronous and synchronous approaches (high hardware cost - peripheral interface chips aren't cheap; slowness - we are essentially operating synchronously with the A/D). As an added drawback, there's the software overhead necessary to initialize the chip and implement the synchronizing software routines. It's possible however, as we'll soon see, to construct totally synchronous and asynchronous interfaces out of common TTL parts costing only 1/3 to 1/2 the price of a peripheral interface chip and requiring none of the software overhead.

The circuits to be presented were built with the LD121A, but are of a sufficiently general nature that they can easily be modified to accommodate the other A/D's in the Siliconix product line.

## LD121A DATA FORMAT

Just to review, Figure 1 shows the output data format of the LD121A digital controller and as you can see, data is BCD and sent out digital serial - bit parallel, perfect for multiplexed displays for which it was designed. The sequence in which the BCD digits are sent out is D5, D4, D3, D2, D1, repeating continuously as indicated. Note that the BCD data for a particular digit is available (16 LD121A clock cycles) both before and after the digit strobe comes on, a feature of which we shall make good use. Sign data appears 250 ns after the D5 strobe and is valid for the duration of D5. Although not shown here, a means of deter-

mining that the A/D has completed a measurement and has new data available is the positive edge of a signal called M/Z which occurs once every measurement interval. Complete LD120/LD121A operational information may be obtained by consulting the data sheet. All of the LD121A digital output signals can drive 1 standard TTL load and the M/Z line — 1/2 a load, a factor which contributed to the use of 74LS parts as much as possible in my circuits.

Since the synchronous interface is the simpler of the two, let's start with it first.

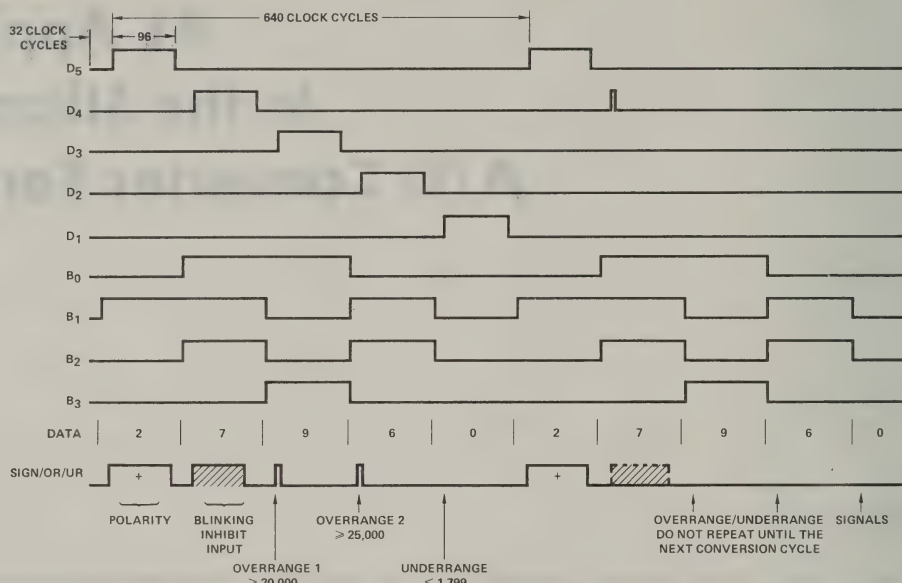


Figure 1. LD121 Digital Output Timing Diagram

## SYNCHRONOUS A/D INTERFACE

In Figure 2 we have the schematic of an LD121A synchronous interface which was built and operated in an Intel SDK-85 system. Key to the operation of this circuit is the READY line which can be found on Intel, MOS Technology and other microprocessors. For those not familiar with it, the READY line is an input to the processor through which slow memories and in this case, slow peripherals can make the processor wait while data to be read in is being placed on the data bus. In this way the processor can be SYNCHRONIZED to the rate at which the slow peripheral is giving data, while running at full speed when other, faster, memories and peripherals are being accessed. The operation of the circuit is as follows. Normally the output to the READY input, A5 pin 5 is high, permitting full-speed processor operation. To accomplish this, all of the inputs to A5 must be low which is possible if none of the first 5 outputs of the 4 to 10 line decoder are active (low). Although the A,

B, C inputs of A2 may change continuously, by using the D input as a chip enable, the outputs in question will remain high. However when a valid chip select (read peripheral operation) comes along, the tristate bus buffer A1 will be enabled as well as the 4 - 10 line decoder. Now depending on the valid address on ADR 0, 1, 2 one of the decoder outputs, corresponding to a particular LD121A digit, will go low. Assuming that all of the digit strobes are low (inactive), the READY line goes low causing the processor to wait up. As soon as the digit strobe in question goes high, indicating valid data is available, the READY line rises again allowing the processor to continue its read operation. Note that the digits may be read in any order as the synchronization is accomplished automatically. However the processor does have to wait for the right digit strobe to come along. The 74LS74 D type F.F. in the circuit is used as an interrupt indicator latch, generating a latched high level interrupt



signal when the positive M/Z edge comes along (new data ready) and resetting when a data read occurs. Depending on how the chip select is generated, the circuit may be set up as regular or memory mapped I/O, the choice is up to the user. As set up, the BCD data is located in the low data nibble and the sign is the high order data bit. However considerable latitude is possible both in data word configuration and parts selection, particularly in choosing the tristate bus buffer and decoder chips.

Lastly, after receipt of a valid chip select there's only a 3 gate delay in generation of a correct READY signal, permitting the circuit to be used with even the fastest of processors providing that they have a READY input.

## ASYNCHRONOUS A/D INTERFACE

In Figure 3 we have the schematic of an asynchronous LD121A interface, also built and operated with an SDK-85. Although it's somewhat more complex than the previous circuit, relatively common parts are used and hardware costs are still well below that of a peripheral interface chip. Briefly, this circuit uses a 2101A memory as a 5 word X 4 bit latch to store the BCD data for immediate access later on by the microprocessor (i.e. no wait states). The 2101A was chosen because of its separate data inputs and outputs and is relatively cheap as far as memories go. Ordinarily LD121A BCD data is being written into the 2101A memory at addresses determined by encoding the LD121A digit strobes into 3 bit binary. The encoding is done by the A4 OR gates and the address is gated to the memory by the A2, A3 AND-NOR gates.

Note that 1/2 of the A3 AND-NOR chip is used to permit the storage of sign information as data bit  $DI_4$  during digit strobe 5. The memory write pulse is generated by A7 and A8 and is a low level pulse of minimum duration so as not to interfere during microprocessor reads (i.e. lock up the A5 read-write arbitrator logic unnecessarily). Note the 0.01  $\mu$ F capacitor on the trigger input to the A8 monostable. It's used to delay the generation of the write enable pulse so that the sign information which is slightly delayed from D5 (by 250 ns) will be valid. A5 is arbitration logic which determines whether a microprocessor read or LD121A data write is to be performed on the 2101A memory. The A5 outputs, pins 3, 6 control the A2, A3 AND-NOR gates and determine whether the 2101A memory address is to be supplied by the system address bus (read) or encoded digit strobes (write). A5 is also set up so that if a data write pulse is present from the monostable, its output pins 3, 6 will not change state (i.e. lock up). However when the write pulse ends, A5 will change state if necessary to reflect whether or not we have a valid chip select present (microprocessor read). If so, it will enable the memory data bus drivers, lock out monostable write pulses and gate the system address bus to the 2101A memory so that the read can be performed. When the chip select is in control of the A5 logic, further updating of the memory by the LD121A is

inhibited until the chip select is removed.

Although I was using a 2101A-2N with a 250 ns access time, measurements showed that data could be obtained within 250 ns after application of a valid chip select, providing that there was no monostable write pulse to lock up the A5 logic at the time. In which case it would have taken 250 ns plus the width of the monostable write pulse. However I found it very difficult to coincidence the chip select and write pulse since the write pulse is so short and so infrequent. So except on very rare occasions, my read access time from application of a valid chip select was at most 250 ns. By being careful about how and when the processor determines that there is new data to be read in (i.e. further qualify the interrupt signal) any possible coincidence of chip select and write pulse can be totally avoided.

As in the previous circuit, the A9-74LS74 is used as an interrupt latch. The entire circuit is of sufficiently general purpose design that the only real limitation to using it with any processor is its 250 ns access time. Again, depending on how the chip select is generated the circuit may be set up as either regular or memory mapped I/O.

Through careful examination of both the asynchronous and synchronous schematics it can be seen that in each, the correspondence between a system address supplied and the BCD digit read is:

ADR 2	ADR 1	ADR 0	Digit
0	0	0	D1
0	0	0	D2
0	1	0	D3
0	1	1	D4
1	0	0	D5

A rough estimate of the savings in time possible using an asynchronous rather than an synchronous interface approach in this application would be something on the order of 1 complete LD121A data output cycle each time we read in all 5 digits. For a LD121A running at maximum clock frequency (250 KHz, 5 conversions/second) this is a savings of about 2.5 milliseconds each and every time. Since the asynchronous circuit acts as though it were memory as far as the processor is concerned, the amount of time necessary to read in new data from it is essentially how quickly the processor can execute memory or I/O read commands, as the case may be, providing of course that read access times are met.

## REFERENCES

1. Intel MCS-85 Users Manual, September 1980 Intel Corporation.

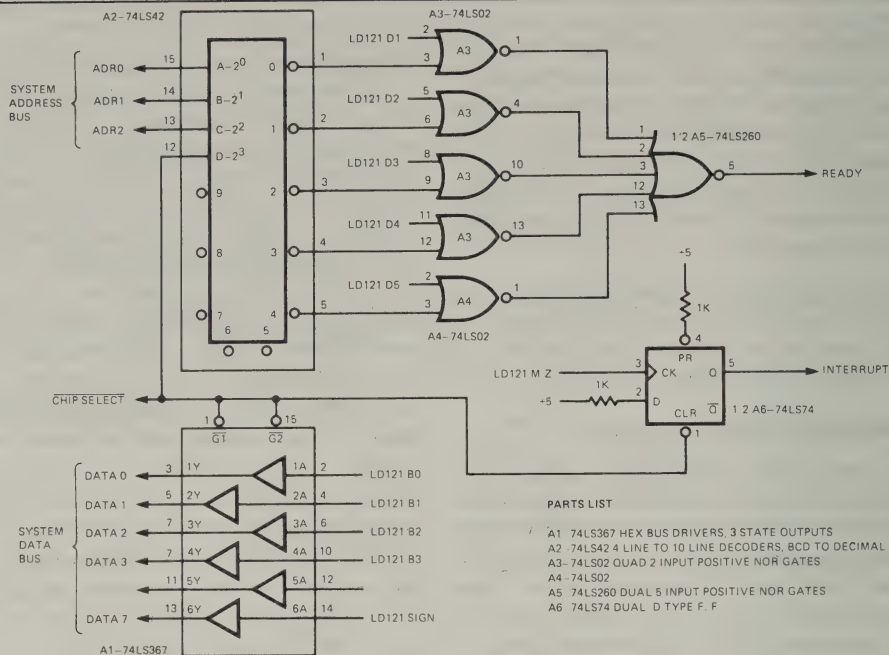


Figure 2. Synchronous Interface

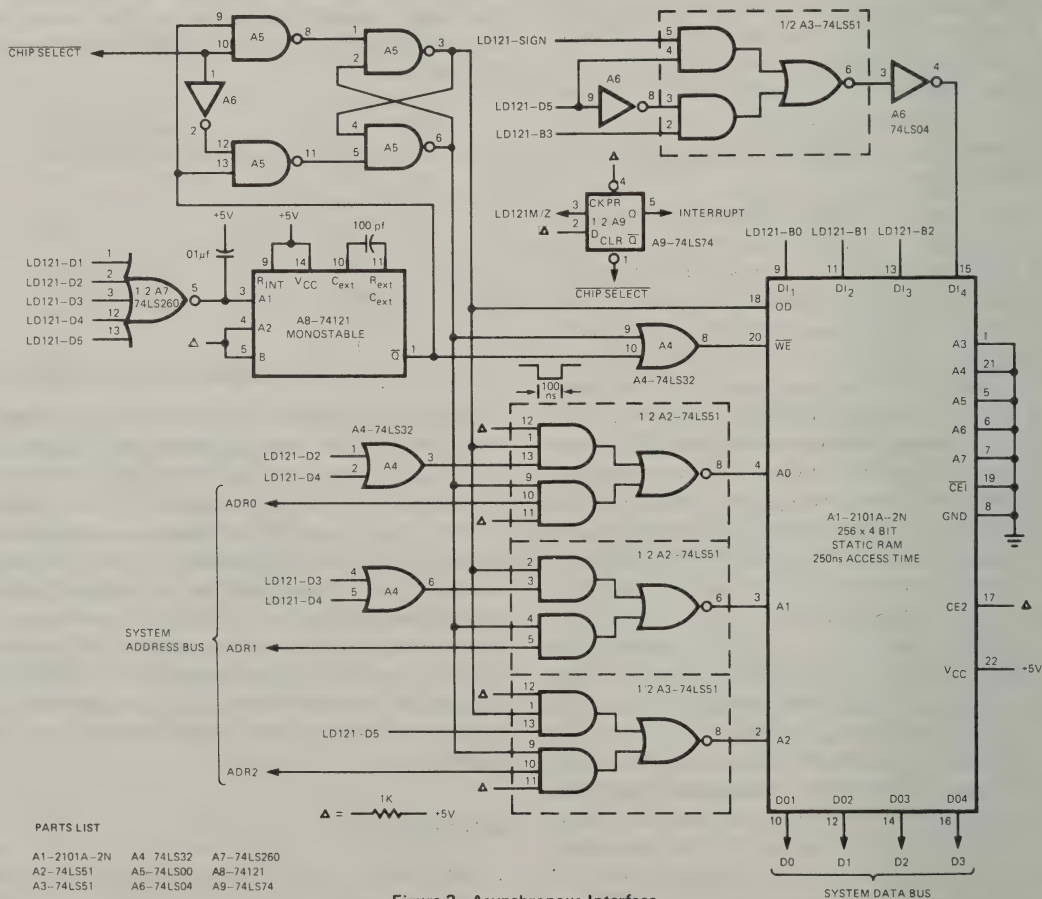


Figure 3. Asynchronous Interface

# 3½ Digit A/D Converter Set

designed for . . .



LD110 LD111A

- High Performance Digital Voltmeters
- Digital Panel Meters
- Digital Instrumentation Readouts
- Microprocessor A/D Interface Subsystem
- Auto-Zeroed Microvolt or Strain-Gauge Systems

## BENEFITS

- Three Usable Ranges with a Single Resistor Change. 1.999 V, 199.9 mV, 19.99 mV
- Excellent System Performance From Basic 0.02% ±1 Count Accuracy
- Wide Sampling Rate: 1/3 to 40/Second
- High Gain Stability (5 ppm/°C) with Buffered Reference Input
- Reduced Signal Loading with MOSFET Input ( $Z_{IN} > 10^9 \Omega$ )
- Auto-Zero System Minimizes Internal and External Offset and Drift Over Temperature
- Auto-Polarity with a Single Reference
- Easy Interface to Displays with Strobed BCD Output Format
- Overrange and Underrange Signals Available

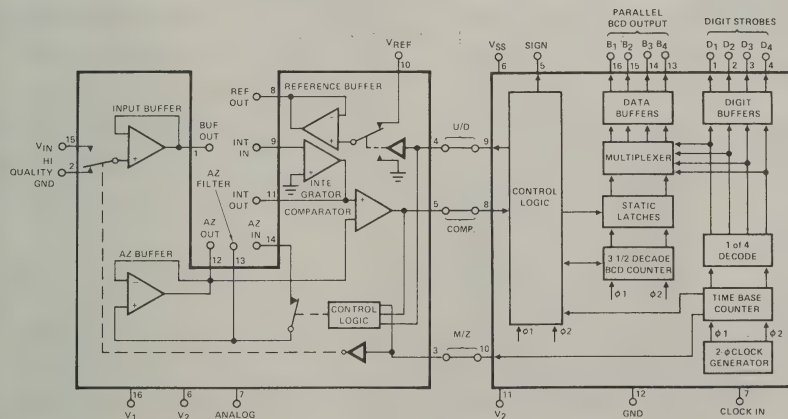
## DESCRIPTION

The "Quantized Feedback" conversion scheme used in the LD110/LD111A set provides an Auto-Zeroing, Auto-Polarity A/D system requiring only a single reference voltage.

The monolithic LD111A high performance analog processor contains a bipolar comparator, a bipolar integrating amplifier, a bipolar reference amplifier, two MOSFET input unity gain amplifiers, several P-channel enhancement mode analog switches and the necessary level shifting drivers to allow the analog and digital processors to be directly interfaced. The high impedance input and reference buffer amplifiers eliminate source loading errors and provide the outstanding temperature coefficient inherent in this system. Break-before-make switch action insures that neither the analog input nor the reference voltage will be shorted to ground at any time.

The PMOS LD110 synchronous digital processor combines the counting, storage and data multiplexing functions with the random logic necessary to control the quantized charge-balancing function of the analog processor. Seventeen static latches store the 3 1/2 digits of BCD data as well as overrange and polarity information. Nine push-pull output buffers (capable of driving one standard TTL load each) provide the sign, digit strobe and multiplexed BCD data outputs, all of which are active high. The digit scan is an interlaced format of digits 1, 3, 2 and 4.

## FUNCTIONAL DIAGRAM



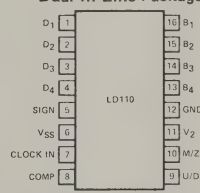
LD111A

LD110

SWITCH STATES ARE FOR A LOGIC "0" AT U/D AND M/Z INPUTS.

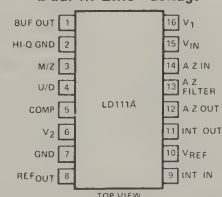
## PIN CONFIGURATIONS

### Dual-In-Line Package



ORDER NUMBER LD110CJ  
SEE PACKAGE 8

### Dual-In-Line Package



ORDER NUMBER LD111ACJ  
SEE PACKAGE 8

7

A/D Converters



## ABSOLUTE MAXIMUM RATINGS

$I_{IN}$ (Pin 15, 2)	$\pm 1$ mA
$V_1 - V_2$ (LD111A)	30 V
$V_{SS}$	6 V
$V_{SS} - V_2$ (LD110)	20 V
V On Any Pin Relative to $V_{SS}$ (LD110)	0.3 V to -20 V
$V_{REF}$	$V_1$

Operating Temperature	0 to 70°C
Storage Temperature	-65 to +125°C
Power Dissipation (Package)*	750 mW

\*Device mounted with all leads welded or soldered to PC board. Derate 6.3 mW/°C above 25°C.

## ELECTRICAL CHARACTERISTICS

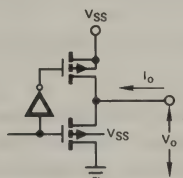
All DC parameters are 100% tested at 25°C. Lots are sample tested for AC parameters to assure conformance with specifications.

Characteristics		Min	Typ	Max	Unit	Test Conditions, Unless Noted: $V_1 = +12$ V, $V_2 = -12$ V, $V_{SS} = 5$ V $V_{REF} = 8.2$ V, $T_A = 25^\circ\text{C}$ , $R_1 = 100\text{K } \Omega$
1	Linearity		0.02		% rdg	
2	Noise		0.1		LSB	Peak-to-Peak Noise Apparent When Going From One Steady Reading to Another
3	Gain T.C.		5		ppm/°C	
4	NMR Normal Mode Rejection		40		dB	$f_{noise} = 60$ Hz
5	$f_{IN}$ Clock Frequency	2	30.7	250	kHz	50% Duty Cycle
6	$r_{DS(on)}$ ON Resistance, Auto Zero Switch		6	20	K $\Omega$	$V_{AZ(in)} = -4.0$ V, $I_S = -30$ $\mu$ A
7	$I_{CL}$ Clock Input Current, Low			-500	$\mu$ A	$V_{CLOCK\ in} = 0.4$ V
8	$I_{IN}$ Input Bias Current		4		pA	$T_A = 25^\circ\text{C}$
9			40			$T_A = 70^\circ\text{C}$
10	$I_{INL}$ Comp. LD110	-1500	-700	-50	$\mu$ A	$V_{IN} = -12$ V
11	$I_{source}$ Reference Buffer	-400	-800		$\mu$ A	$V_{INL} (U/D) = 0.8$ V, $V_{OUT} = 0$
12	$I_{sink}$ AZ Buffer		800			$V_{AZ} = -4$ V, $V_{OUT} = 0$ V
13	$I_{sink}$ Input Buffer	400	800			$V_{IN} = -2$ V, $V_{OUT} = 0$ V
14	$I_{source}$ Input Buffer	-50	-100			$V_{IN} = 2$ V, $V_{OUT} = 0$ V
15	$V_{offset}$ AZ Buffer	-100		100	mV	$V_{OUT} = 0$ V
16	$V_{OL1}$ Measure/Zero Voltage, Low			0.6	V	$I_{OL} = 150$ $\mu$ A
17	$V_{OH1}$ Measure/Zero Voltage, High	2.4				$I_{OH} = -200$ $\mu$ A
18	$V_{OL2}$ Up/Down Logic Voltage, Low			0.6		$I_{OL} = 250$ $\mu$ A
19	$V_{OH2}$ Up/Down Logic Voltage, High	2.4				$I_{OH} = -200$ $\mu$ A
20	$V_{OH3}$ Analog Comparator Voltage	2.4				$I_{OH} = -100$ $\mu$ A
21	$V_{OL3}$ Digits, Bits, Voltage, Low			0.6		$I_{OL} = 1.6$ mA
22	$V_{OL4}$ Sign Voltage, Low			0.65		$I_{OL} = 1.6$ mA
23	$V_{OH4}$ Data Bits Voltage, High	2.4				$I_{OH} = -200$ $\mu$ A
24	$V_{OH5}$ Digits, Sign Voltage, High	2.4				$I_{OH} = -800$ $\mu$ A
25	$I_1$ Supply Current		2.2	4.0	mA	
26	$I_{2A}$ Supply Current, LD111A		-1.8	-4.0		
27	$I_{2D}$ Supply Current, LD110		-17	-23		
28	$I_{SS}$ Supply Current		17.4	24		
29	PSRR <sub>1</sub> Power Supply Rejection Ratio, $V_1$	80	85		dB	
30	PSRR <sub>2</sub> Power Supply Rejection Ratio, $V_2$	60	65			
31	Reference Voltage Rejection		1		% $\Delta$ rdg/ $\Delta V_{REF}$	$R_{REF} = R_2 = 100\text{K } \Omega$ , $V_{IN} = 2$ V

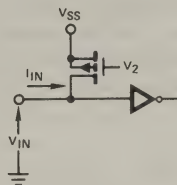
Typical values are for DESIGN AID ONLY, not guaranteed and not subject to production testing LD110 IPANII LD11A CMAMI-A



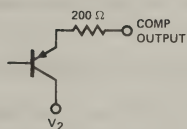
## INPUT/OUTPUT SCHEMATICS



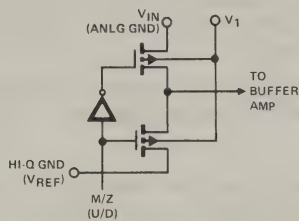
**LD110 OUTPUT BUFFERS**  
(Digits, Bits, Sign, M/Z, U/D)



**LD110 COMPARATOR, CLOCK INPUTS**



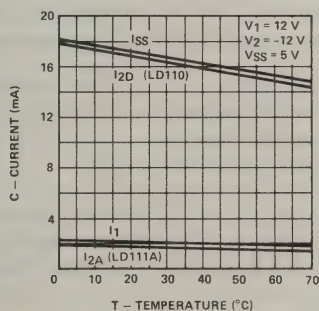
**LD111A Comparator Output**



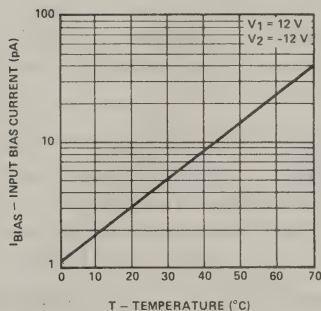
**LD111A Inputs ( $V_{IN}$ ,  $V_{REF}$ )**

## TYPICAL CHARACTERISTICS

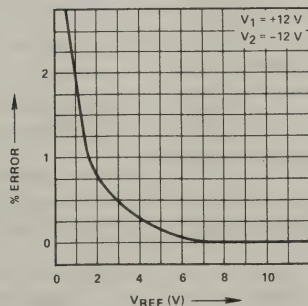
Supply Currents vs  
Temperature



Input Bias Current vs  
Temperature



Ratio Operation  
( $V_{IN}/V_{REF} = \text{Constant}$ )



## DESCRIPTION OF PIN FUNCTIONS — LD111A

**BUF OUT** — The output of this unity gain input buffer amplifier is applied to the integrator summing node through a scaling resistor  $R_2$ . The value of this resistor is typically  $10K \Omega$  for a 200.0 mV full scale and  $100K \Omega$  for a 2.000 V full scale. The digital output is inversely proportional to the value of this resistor.

$$\text{Count} = \frac{V_{IN}}{V_{REF}} \cdot \frac{R_1}{R_2} \cdot 8192$$

**HI-QUALITY GND** — This pin, typically connected to a High Quality Ground point for single ended inputs *can be used as the inverting input for differential signals*. The digital output will be  $V_{IN} - V_{HI-Q}$ . When using this differential mode, it is important that resistor  $R_3$  be less than resistor  $R_2$  for proper operation.

**M/Z** — Measure/Zero Logic Input. Internal level shifting drivers operate the PMOS switches in response to this digital signal.

**U/D** — Up/Down Logic Input. The logic signal applied to this pin operates a SPDT switch to provide Quantized pulses of charge to the integrator.

**COMP** — This analog comparator output is an open collector configuration which goes to  $V_2$  when "low."

**$V_2$**  — Negative Supply Voltage. Recommended level is  $-12 V \pm 10\%$ .

**GND** — Analog Processor Ground. Should be kept separate from Digital Grounds.

**REF<sub>out</sub>** — This buffered voltage output of the SPDT U/D switch, converted to a current by resistor  $R_1$ , supplies the reference current to the integrator.

**INT. IN** — Integrator Summing Node.

**$V_{REF}$**  — A stable positive reference voltage (2 to 10 V) applied to this pin is the standard to which the input voltage  $V_{IN}$  is measured. Ratio measurements can be made by applying a variable to this input (1.0 to 10 V).

**INT. OUT** — The output of the integrating amplifier is made available for application to the Auto-Zero amplifier by means of resistor  $R_4$ .

**AZ OUT** — The output of the unity gain Auto-Zero amplifier provides a second negative reference current to the integrator through resistor  $R_3$ .

**AZ FILTER** — The Auto-Zero Capacitor ( $C_{AZ}$ ) connected to this pin stores D.C. voltage components to balance amplifier offset and drift components.

**AZ IN** — This input is switched into the AZ filter during the zeroing interval.

**$V_{IN}$**  — Analog Voltage Input. The A/D System digitizes the voltage appearing at this input.

**$V_1$**  — Positive Supply Voltage. The recommended level is  $+12 \text{ volts} \pm 10\%$ .

## DESCRIPTION OF PIN FUNCTIONS—LD110

**$V_{SS}$**  — Positive Supply Voltage. Recommended level is  $+5 V \pm 10\%$ .

**$V_2$**  — Negative Supply Voltage. Recommended level is  $-12 V \pm 10\%$ .

**CLOCK IN** — This input accepts a TTL or MOS level clock to drive the synchronous digital circuitry. Acceptable duty cycles on the external clock range from 30% high, 70% low to 70% high, 30% low for clock frequencies from 2 kHz to 250 kHz. Although any clock frequency between 2 kHz and 250 kHz may be used, clock frequencies that are integer divisions of 2048F<sub>L</sub> ( $F_{IN} = 2048F_L/n$ ,  $n = 1, 2, 3, \dots, 51$ ), ( $F_L$  = Line Frequency) provide measure and zero periods that are integer multiples of the line frequency period ( $T_{zero} = n/F_L$ ,  $T_{measure} = 2n/F_L$ ). Line frequency interference is minimized by the selection of one of these 51 frequencies.

This input has an active pull-up to  $V_{SS}$ .

**M/Z** — Measure/Zero Logic Output. This 0 to 5 volt logic output successively provides Autozero and Measurement intervals of 2048 and 4096 clock periods respectively. This output is compatible with CMOS logic and directly interfaces with the LD111A analog processor.

**U/D** — Up/Down Logic Output. This output has logic levels of 0 and +5 volts to provide pulse-width modulation of the reference current when used with the LD111A analog processor. This output is CMOS compatible.

**COMP** — Analog Comparator Input. This input has an active pull-up to  $V_{SS}$  for a comparator "high" state. This pin must be pulled down to  $V_2$  for a "low" comparator state.

An End-of-Conversion Signal can be decoded from the three interconnecting logic lines (M/Z, U/D, Comp) using the following CMOS logic.

$$\overline{M/Z + U/D + \text{Comp}} = E.O.C.$$

**$B_1, B_2, B_3, B_4$**  — BCD Data Bit Output.  $B_4$  represents the most significant bit and  $B_1$  the least significant bit of the BCD output. Bit 4 of digit 4 goes high for an underrange condition (less than 100 counts). These outputs are compatible with 1 standard TTL load.

$$\text{MUX Underrange} = B_4 \times D_4 \text{ (5\% of full scale)}$$

**$D_1, D_2, D_3, D_4$**  — Digit Strobe Outputs.  $D_4$  is the most significant and  $D_1$  the least significant digit of the 3 1/2 digit output. The digit strobes are each selected in turn when the BCD data bits for that digit appear at the bit outputs (see Figure 4).

$$\text{MUX Overage} = \overline{D_1 + D_2 + D_3 + D_4} \\ \text{(100\% of full scale, count} \geq 2000\text{)}$$

**SIGN** — Sign of Analog Input Polarity. This TTL level output is a static signal which is either 0 or  $V_{SS}$  for a negative or positive input polarity respectively.

**GND** — Digital Processor Ground. Should be kept separate from Analog Grounds. Common connection should be made at the power supply.

## FUNCTIONAL OPERATION

The Connection Diagram of Figure 1 should be referred to along with the timing diagrams of Figures 2, 3, and 4 in this discussion of functional operation.

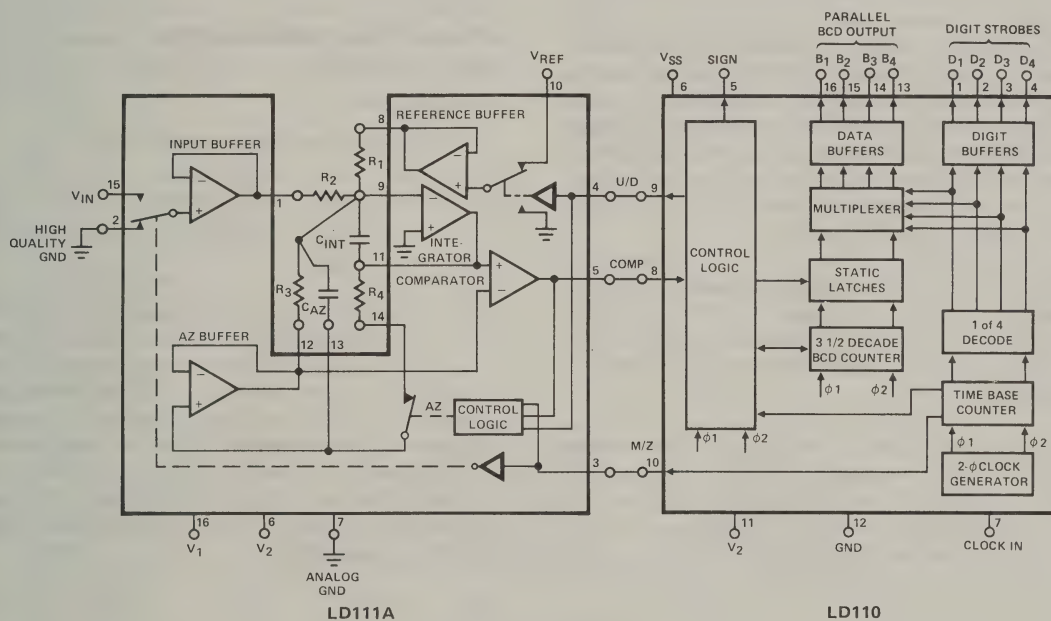
**Time Base Counter:** An external clock signal using either TTL or MOS logic levels drives a 2- $\phi$  clock generator on the synchronous digital chip. The clock frequency is divided by the time base counter into sampling intervals of 6144 pulses of which 4096 constitute the measurement interval and 2048 the auto-zero interval. Intermediate frequency divisions are utilized by both the control logic and the 1 of 4 decoder for the digit enables and bit scan.

## AUTO-ZERO INTERVAL

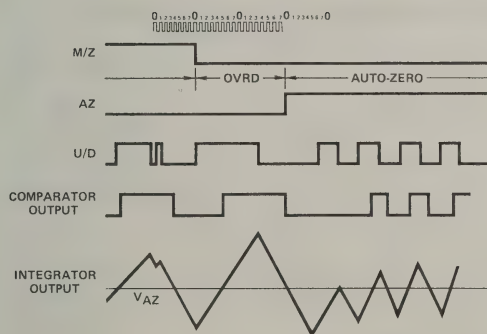
The Auto-Zero interval provides a means to null out the offset voltages of the amplifiers used in the LD110/LD111A system. In addition, it automatically establishes a second

tracking reference voltage necessary for bipolar A/D conversion.

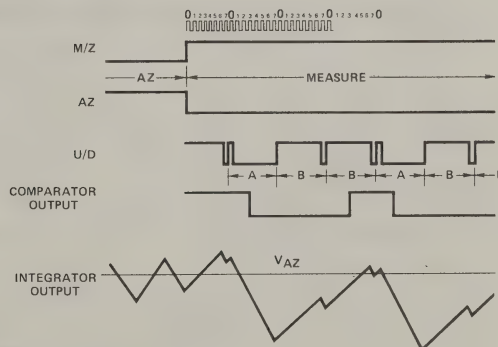
The Auto-Zero sequence is initiated when the M/Z (Measure/Zero) signal switches the input buffer amp to analog ground. After a brief count-correcting override period, the AZ switch is closed connecting the AZ amplifier and integrator together in a closed-loop second-order system. During this time the control logic ignores the comparator output and pulses the U/D switch at a 50% duty cycle of 4 clock periods "Up" and 4 "Down" (see Figure 2). Equilibrium of this closed-loop system is attained when the average currents through  $R_1$  and  $R_3$  are equal and opposite. This is achieved when  $V_{AZ}$ , the Auto-Zero voltage, is equal to  $-\frac{1}{2} V_{REF}$  ( $R_1 = R_3$ ). Establishing  $V_{AZ}$  and storing it on  $C_{AZ}$  gives the U/D logic the capability of switching either a + or - reference current to the integrator during conversion. Thus when U/D is "Up,"  $I_1 + I_3 = -V_{REF}/2R_1$  and when U/D is "Down,"  $I_1 + I_3 = V_{REF}/2R_1$ . The Auto-Zero interval is of sufficient duration to insure that  $V_{AZ}$  will be well established.



Connection Diagram  
Figure 1



Auto-Zero Timing  
Figure 2



Measure Interval Timing  
Figure 3



## FUNCTIONAL OPERATION (Cont'd)

## MEASUREMENT INTERVAL

The "Quantized Feedback" conversion system is characterized by a single phase Digitization interval in which a digital control system feeds back quantized units of charge in response to the sampled state of an analog comparator. These quanta of charge balance the charge being supplied to the integrator by the analog voltage. The magnitude ( $V_{REF}/2R_1 \times 6/f_{clock}$ ) of the Quantized charge being fed back and its sign (+ or -) arise from the fact that the control logic has two U/D duty cycles available during the Measure interval as shown in Figure 3.

The U/D logic is "up" one clock cycle and "down" 7 cycles for a high comparator output in the clock cycle preceding a set of 8 cycles. This will be designated duty cycle "A." With a low comparator output in clock cycle number 7 the U/D logic will be "up" for 7 cycles and "down" for 1 cycle in the following 8 clock cycles. This is duty cycle "B." The effect of these two reference current duty cycles on the integrator output is shown in Figure 3. It can be seen that the "up" state of the U/D logic drives the integrator output voltage up. The up/down BCD counter increments by each clock pulse when the U/D logic is "up" and decrements by each clock pulse when the U/D logic is "down." Consequently the net count goes up 6 counts for a "B" duty cycle and down 6 for an "A" duty cycle.

Input polarity is determined by the first appearance of two consecutive duty cycles of the same type. The control logic would determine the analog input to be negative if two "A" duty cycles occur in succession and positive if two "B" duty cycles occur in succession.

Since the counting process is done by increments (or decrements) of 6 during the measure interval, a short override interval is required at the end of the Measurement to "fine tune" the count to the nearest LSB. This occurs within the first 32 clock periods of the AZ interval.

## DATA FLOW

Following the count correcting override sequence; the contents of the BCD counters and sign flip-flop are loaded into the internal latches. Counter states of less than 100 or greater than 1999 are decoded as underrange or overrange conditions respectively. The underrange signal is forced on Bit 4 during  $D_4$  time. The overrange signal will be used to blank the display during the zero interval giving a visual overrange cue by means of a blinking display.

The BCD data stored in the latches is continuously scanned every 32 clock periods (8 clock times per digit). This data format is shown in Figure 4. Sign information is available as a static signal on a separate pin (high for +, low for -).

The BCD data output is an interlaced scan of digits 1, 3, 2, and 4 where digit 4 is the most significant digit. All outputs are active high and TTL compatible.

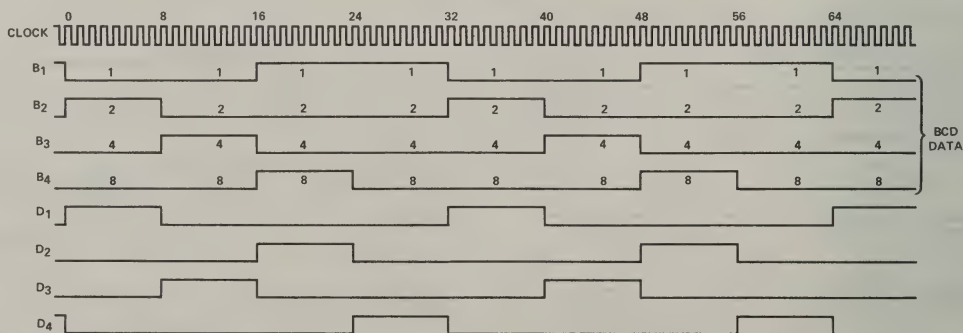
APPLICATIONS INFORMATION  
(Refer to Figure 5)

## 1. Power Supplies

- a) The recommended supply voltages are:

$V_1$	= 12 V $\pm 10\%$
$V_2$	= -12 V $\pm 10\%$
$V_{SS}$	= 5 V $\pm 10\%$
$V_{REF}$	= 2.00 V to 10 V

Operation is possible with  $V_1$  and  $V_2$  supplies from  $\pm 9$  V to  $\pm 15$  V. These minimum voltages ( $\pm 9$  V) require that the LD110/LD111A system be operated on the 200.0 mV scale to maintain input buffer linearity. It should be realized that operation below  $\pm 10.8$  volts is not guaranteed.  $V_2$  voltages greater than -13.2 V allows the LD110 to dissipate a considerable amount of power (400 mW, warm to the touch). A 150  $\Omega$  resistor in series with pin 11 of the LD110 will limit the current resulting in cooler operation and longer life with large values of  $V_2$ .



Data Output Format (Output = 1492)  
Figure 4



## APPLICATIONS INFORMATION (Cont'd)

**2. Input Protection.** Under normal operating conditions the inputs of the LD111A should not be exposed to a voltage exceeding either  $V_1$  or  $V_2$  (see absolute maximum ratings). In many applications however, such as a DMM/DVM, the  $V_{IN}$  or  $V_{REF}$  input may have a high voltage source connected which is capable of supplying destructive currents into the LD111A. To prevent such an occurrence, a current limiting resistor should be placed in series with the appropriate input pin. The 1 mA maximum current rating should be observed. A  $1\text{ M}\Omega$  resistor in series with pin 15 of the LD111A would offer input protection up to a 1000 V overvoltage.

**3. Operation Over the Full Sampling Range.** Any sampling rate from 1/3 to 40 samples/second can be accommodated by simply changing the values for  $C_{INT}$  and  $C_{AZ}$  ( $R_3$  and  $R_4$  will remain as shown in Figure 5).

To find the proper value for  $C_{INT}$  and  $C_{AZ}$ , (shown as  $C_1$  and  $C_2$  respectively on Figure 5) find the needed clock frequency for a specific sampling rate from the following relationship.

$$f_{\text{clock}} = \text{Sampling Rate} \times 6144$$

Once the clock frequency has been determined, the values for  $C_{INT}$  and  $C_{AZ}$  can be found.

$$C_{INT} \cong \frac{200 \mu\text{F/sec}}{f_{\text{clock}}}$$

$$C_{AZ} \cong 10 C_{INT}$$

**4. Resistor Selection.** Resistor  $R_2$  is the scaling resistor and is selected to provide .10 nA per LSB into the integrator summing junction. Thus,

$$\begin{aligned} R_2 &= \frac{V_{IN}(\text{Full Scale})}{(2000 \text{ Counts}) (10 \text{ nA/Count})} \\ &= 100\text{K } \Omega \text{ (2.000 V Scale)} \\ &= 10\text{K } \Omega \text{ (200.0 mV Scale)} \\ &= 1\text{K } \Omega \text{ (20.00 mV Scale)} \end{aligned}$$

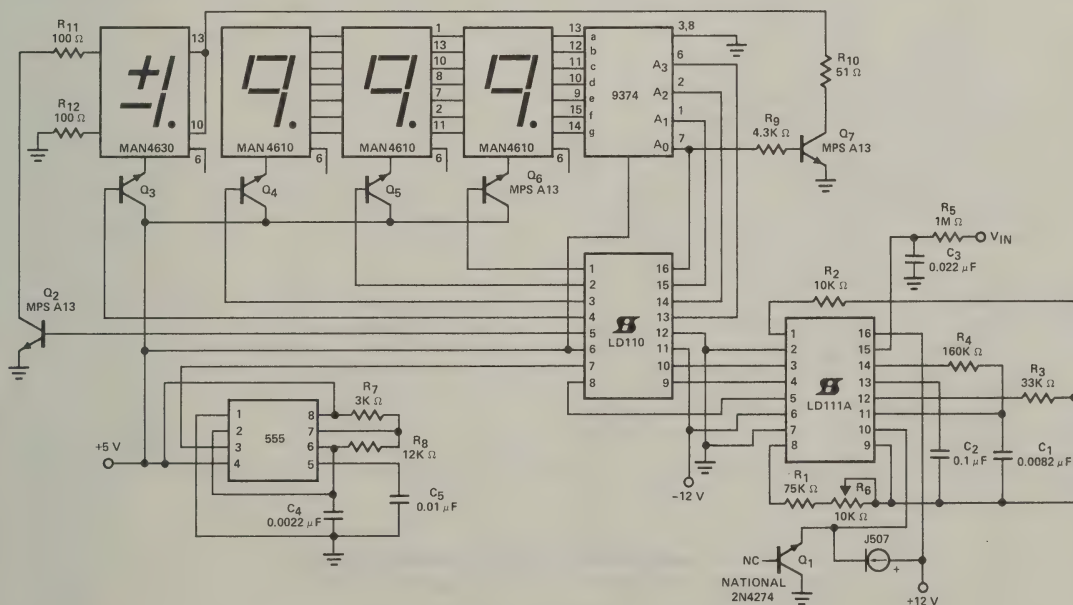
The reference resistor  $R_1$  is chosen to satisfy the relationship

$$R_1 = \frac{V_{REF}}{81.92 \text{ V}} \text{ M } \Omega \text{ (Trimmed)}$$

**5. 20.00 mV Scale (10  $\mu\text{V}$  Resolution).** The improved noise performance of the LD111A allows it to be used in a 20.00 mV DPM when  $R_2$  is selected to be  $1\text{K } \Omega$ . This high resolution range, while useful, does not have the same degree of zero and LSD stability as the 200.0 mV and 2.000 V ranges. Extreme care in layout is required to minimize noise and offsets at  $V_{IN}$  and Hi-Q GND.

**6. Ratio Operation.** The LD110/LD111A is a ratio measuring system — the output being

$$\text{Count} = \frac{V_{IN}}{V_{REF}} \frac{R_1}{R_2} \quad 8192$$



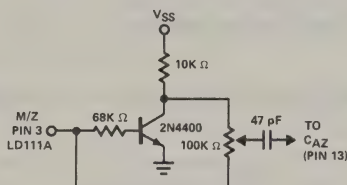
3 1/2 Digit DVM ( $\pm 200.0 \text{ mV}$ ) Common Anode Display

Figure 5

## APPLICATIONS INFORMATION (Cont'd)

The high impedance input and reference buffer amplifiers offer a system with ratio operation and minimal source loading. The ratio curve shown with the typical characteristics illustrates the ratio performance.

**7. Zero Adjustment.** The LD110/LD111A converter set is an Auto-zeroing system. Many applications exist, however, in which a means of nulling out external offsets is needed. The circuit of Figure 6 provides this offset nulling feature.

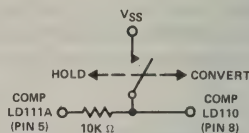


Offset Nulling Circuit  
Figure 6

**8. Replacing the LD111 with the LD111A.** The LD111A offers a significant improvement in linearity, noise and temperature stability over the LD111. It also eliminates the need for the integrator clamp zener required on the LD111. The LD111A is a plug-in replacement for the LD111.

**9. Data Valid (End-of Conversion).** The BCD data from the LD110 is changed only once per conversion, at the end of the override interval. The  $3\frac{1}{2}$  digits of data are then repeatedly multiplexed out during the rest of the zero and for the full Measure Interval. Since the data cannot change during the Measure Interval and since the Measure Interval occurs once each sampling interval, this high state of the M/Z line can be used as a Data Valid or End-of-Conversion signal.

**10. "Hold".** The last conversion of the LD110/LD111A may be held indefinitely by means of the added circuitry shown in Figure 7. Forcing the comparator input of the LD110 to the high state eliminates any future data transfers. The resistor protects the LD111A comparator output. Opening the connection to  $V_{SS}$  allows normal comparator action and data transfer. The first conversion after a "hold" will always be in error since the AZ voltage has not been maintained during "hold".



"Hold" Circuit  
Figure 7

# Function/Application of the LD110/LD111 3½ Digit A/D Converter Set

*Replace LD111 with LD111A  
for New Designs*

AN74-1 (LD110/LD111)

7  
A/D Converters

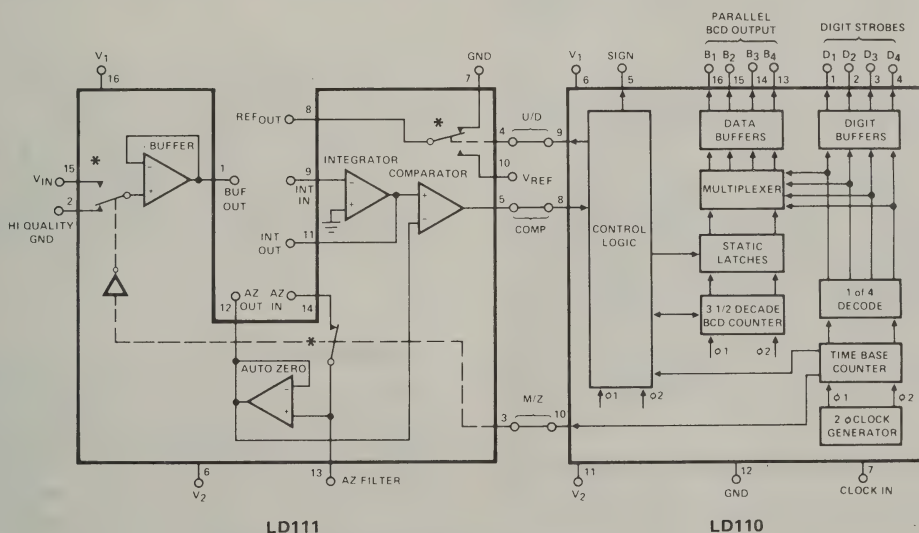
## INTRODUCTION

The Siliconix LD110/LD111 3½-digit A/D converter integrated circuit set offers high performance and versatility with a minimum of required external circuitry. The set consists of a monolithic PMOS synchronous digital processor (LD110) and a monolithic bipolar-PMOS analog processor (LD111). The salient features of the A/D converter set include an accuracy of 0.05% (of reading)  $\pm 1$  count; a 4 pA typical input bias current; an input impedance of greater than 1,000 M $\Omega$ ; autozeroing; and a single reference voltage requirement. External user-selected components will allow for two different voltage ranges (2,000 V and 200.0 mV) and a wide range of sampling rates (1/3 to 12 samples per second) to accommodate a variety of applications.

This Application Note describes the functional operation of the LD110/LD111 A/D converter chip set, provides a basis for criteria in external component selection, and offers some practical circuit applications.

## Functional Operation

The conversion technique balances the charge supplied by a current proportional to the input voltage, over a measure interval, with an accumulation of quantized charges equal to a BCD count. The units of quantized charge are provided through pulsewidth modulation of a reference current. In Figure 1, the A/D converter set is shown with the external RC components required to analyze the functional operation.

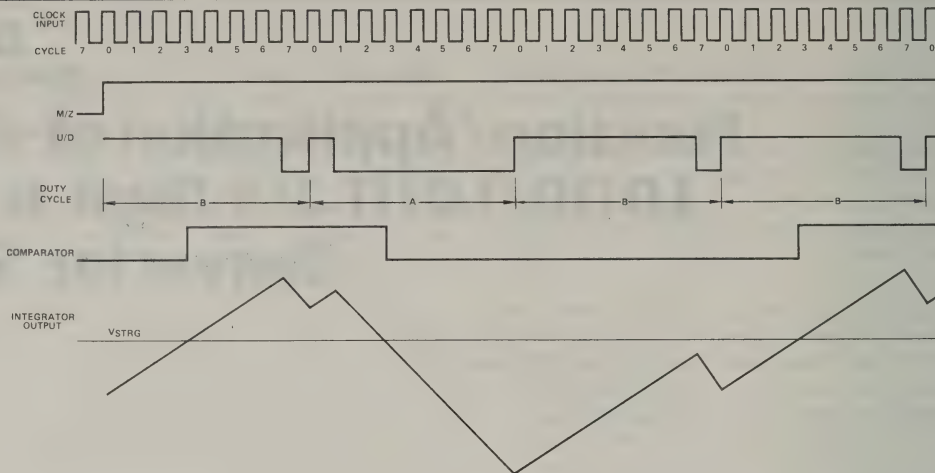


\* P-channel Enhancement Mode MOS-FET Switches

U/D Shown in Down State (logic "0") M/Z in Zero State (logic "0")

Functional Diagram  
Figure 1





Measure Interval Timing  
Figure 2

The clock frequency is divided by the time-base counter of the LD110 digital processor into sampling intervals of 6144 cycles; 4096 cycles constitute the measurement interval and 2048 cycles make up the auto-zero interval.

The auto-zero interval allows the effects of offset, temperatures and drift to be impressed on the auto-zero storage voltage,  $V_{strg}$ , which is maintained as a reference by  $C_{strg}$ . Therefore, during the succeeding measure interval these effects will be balanced out. In addition,  $V_{strg}$  acquires a voltage component available at the AZ amplifier output, which provides a current equal to  $-\frac{1}{2} V_{REF}/R_1$  through resistor  $R_3$ . The net current provided to the integrator summing node by the sum of  $V_{strg}/R_3$  and the current through  $R_1$  is either + or  $- V_{REF}/2R_1$ , depending on the position of the Up/Down switch. The input of the buffer amplifier is grounded during this interval.

The input voltage  $V_{IN}$  is applied to the input buffer amplifier during the measure interval. This amplifier, in conjunction with  $R_2$ , supplies an additional current  $V_{IN}/R_2$  to the integrator summing node. The comparator transmits the state of the integrator output (with respect to  $V_{strg}$ ) to the control logic. The control logic attempts to establish equilibrium in the circuit by operating the Up/Down switch at one of the two available duty cycles (7 clock cycles UP, one cycle DOWN; 1 clock cycle UP, 7 cycles DOWN) while the counter keeps track of the net UP count. The integrator output, Measure/Zero (M/Z), Up/Down (U/D) and comparator levels during the measure interval are shown in Figure 2.

The following equations describe the measurement technique:

$$\Delta Q = 0$$

WHERE:

$$\Delta Q = \frac{V_{IN}}{R_2} \Delta t_{measure} - \frac{V_{REF}}{2R_1 f_{IN}} (N_U) + \frac{V_{REF}}{2R_1 f_{IN}} (N_D) \quad (1)$$

WHERE:

$$(N_U) = (\text{\# counts UP}) \text{ and}$$

$$(N_D) = (\text{\# counts DOWN})$$

BUT:

$$\# \text{ counts UP} + \# \text{ counts DOWN} = 4096 \text{ (clock cycles in the measure interval)} \quad (2)$$

$$\# \text{ counts UP} - \# \text{ counts DOWN} = \text{net count} \quad (3)$$

THEN:

$$0 = \frac{V_{IN}}{R_2} \Delta t_{measure} - \frac{V_{REF}}{2R_1 f_{IN}} (\text{net count}) \quad (4)$$

BUT:

$$\Delta t_{measure} = 4096/f_{IN} \quad (5)$$

Substituting and multiplying by  $f_{IN}$  yields

$$\text{Net count} = V_{IN} \cdot \frac{R_1}{R_2} \cdot \frac{8192}{V_{REF}} \quad (6)$$

Equation (6) is fundamental to the application of the LD110/LD111 A/D converter set.

### Component Selection

Application of the LD110/LD111 A/D converter set should begin with the selection of power supplies and the clock frequency. The recommended supply voltages are  $V_1 = 12 \text{ V} \pm 10\%$ ,  $V_2 = -12 \text{ V} \pm 10\%$  and  $V_{SS} = 5 \text{ V} \pm 10\%$ . Clock frequencies between 2 kHz and 75 kHz are recommended. The duty cycle of the clock is not of particular importance; the logic "0" time should however, be greater than 5  $\mu\text{sec}$ . The sampling rate and clock frequency are related as follows:

$$\text{Sampling Rate} = f_{IN}/6144 \quad (7)$$



The clock frequency may be chosen to minimize line frequency interference. If the auto-zero and measurement periods are integral multiples of the line frequency ( $f_L$ ) period, line frequency rejection will be maximized:

$$\Delta t_{\text{ZERO}} = 2048/f_{\text{IN}} \quad (\Delta t_{\text{measure}} = 2 \Delta t_{\text{zero}}) \quad (8)$$

$$\frac{2048}{f_{\text{IN}}} = \frac{n}{f_L}, \text{ where } n = 1, 2, 3, \dots 51 \quad (9)$$

THEN:

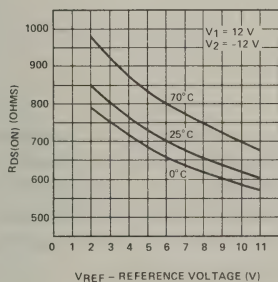
$$f_{\text{IN}} = \frac{2048 f_L}{n} \quad (10)$$

Once the clock frequency is chosen, the proper values for the external RC components may be determined.

Equation (6) defines the relationship between the ratio  $R_1/R_2$  and the reference voltage  $V_{\text{REF}}$  when a full-scale voltage range  $V_{\text{IN}}(\text{F.S.})$  is chosen. This relationship is:

$$\frac{R_2}{R_1} = \frac{V_{\text{IN}}(\text{F.S.})}{2000} \frac{8192}{V_{\text{REF}}} \quad (11)$$

It is usually more convenient to select  $V_{\text{REF}}$  before assigning resistance values because of the implications of temperature coefficients, availability, or other considerations.  $V_{\text{REF}}$  should be greater than 5 V, but less than  $V_1$ . As  $V_{\text{REF}}$  is increased the U/D switch ON resistance decreases, as is shown in Figure 3.  $R_1$  also increases with  $V_{\text{REF}}$ , thus decreasing the proportion of the total resistance provided by  $R_{\text{DS(ON)}}$ . Consequently, a large  $V_{\text{REF}}$  minimizes the effects of the U/D switch ON resistance. It is very important that  $V_{\text{REF}}$  have a low temperature coefficient to minimize drift and the resulting count error.



$R_{\text{DS(ON)}}(\text{U/D Switch})$  vs.  $V_{\text{REF}}$  and Temperature  
Figure 3

Equation (12) shows the change in count which will occur for a fractional change in  $V_{\text{REF}}$  (see Appendix A, Page 10)

$$\Delta \text{count} = -2000 \frac{V_{\text{IN}}}{V_{\text{IN}}(\text{F.S.})} \frac{\Delta V_{\text{REF}}}{V_{\text{REF}}} \quad (12)$$

Consequently, the count will decrease by 1 for each +0.05% change in  $V_{\text{REF}}$ , for  $V_{\text{IN}} = V_{\text{IN}}(\text{F.S.})$

$R_2$  should be chosen to supply a full scale current of  $20 \mu\text{A}$  into the integrator summing node ( $100 \text{ K}\Omega$  for  $2.000 \text{ V}$  and  $10 \text{ K}\Omega$  for  $200.0 \text{ mV}$ ).  $R_1$  can then be determined by Equation (11).  $R_1$ ,  $R_2$  and  $V_{\text{REF}}$  and the basic temperature-sensitive components of the system. The auto-zero interval makes the system essentially independent of changes in  $C_{\text{INT}}$ ,  $R_3$ ,  $R_4$ ,  $R_5$ ,  $C_{\text{strg}}$  and the offset voltages of the amplifiers. In Figure 3, note that the U/D switch ON resistance has a temperature coefficient of about  $0.2^\circ\text{C}$ . This temperature-dependent resistance must be considered as a part of  $R_1$ , the reference resistor. The error in count resulting from a change in this total resistance  $R_1$  is examined in Appendix B (Page 10) and found to be:

$$\Delta \text{Count} = 2000 \frac{V_{\text{IN}}}{V_{\text{IN}}(\text{F.S.})} \frac{\Delta R_1}{R_1} \quad (13)$$

Since the count is proportional to the ratio  $R_1/R_2$ , equal temperature coefficients for these resistors should allow this ratio (and the count) to be maintained even with a change in the ambient temperature. It is desirable, however, to use resistors with low temperature coefficients for  $R_1$  and  $R_2$  to reduce any errors resulting from the differences in these coefficients.

The net error that can be attributed to temperature effects is the sum of the errors due to the changes in  $V_{\text{REF}}$  and the  $R_{\text{DS(ON)}}$  of the U/D switch. Temperature compensation for the A/D converter circuit, then, can be approached in two different ways. The first method would be to provide a large  $V_{\text{REF}}$  (less than  $V_1$ , however) with a very low temperature coefficient. This would require a large value of resistance for  $R_1$ , reduce  $R_{\text{DS(ON)}}$  and make changes in  $R_{\text{DS(ON)}}$  negligible. The alternative method is to note that a reference voltage with a positive temperature coefficient produces an error in the count which tends to oppose the error caused by the positive temperature coefficient of  $R_{\text{DS(ON)}}$ . Thus the two effects can be used to counteract one another (an example is provided in Appendices A and B).

The specified accuracy of the A/D converter will be maintained if the integrator capacitor  $C_{\text{INT}}$  is chosen so that the voltage swing of the integrator is held to within  $0.75 \text{ volt}$  of  $V_{\text{strg}}$ . An analysis of this constraint, shown in Appendix C, (Page 11) results in the following relationship for  $C_{\text{INT}}$ :

$$C_{\text{INT}} = \frac{28.5 V_{\text{IN}}(\text{F.S.})}{R_2 f_{\text{IN}}} \quad (14)$$

This capacitor and the zener diode to be placed in parallel with it should have a combined leakage of less than  $10 \text{ nA}$  (see Appendix D, Page 11) to minimize this possible source of error.

The storage voltage,  $V_{\text{strg}}$ , should be maintained between  $-2 \text{ V}$  and  $-5 \text{ V}$  for normal operation. The ON resistance of

the auto-zero (AZ) switch is typically 11 K $\Omega$  at  $V_{strg} = -4$  V ( $V_2 = -12$  V), and will increase significantly with an increasingly negative storage voltage. Resistor  $R_3$  can be selected to provide the desired  $V_{strg}$  by using Equation (17). The integrator output, which swings around  $V_{strg}$  during the measure and zero intervals, must always be more positive than  $-9$  V to maintain the functionality of the analog processor. This can be accomplished by placing back-to-back Zener diodes in parallel with  $C_{INT}$  (the second diode is to prevent the Zener from being forward biased). It then becomes important that the integrator output voltage not exceed the breakdown voltage of the Zener diodes, for the maximum input voltage for which an accurate readout is desired. The relevant equations are:

$$V_{o(min)} > -V_{zener} \quad (15)$$

WHERE:

$$V_{o(min)} = V_{strg} - \frac{7}{f_{IN} C_{INT}} \left[ \frac{V_{REF}}{2R_1} + \frac{V_{IN(max)}}{R_2} \right] \quad (16)$$

(see Appendix C)

$$V_{strg} = \frac{-V_{REF}}{2} \frac{R_3}{R_1} - \frac{R_3}{R_2} V_{Hi-Q} \text{ (If Hi-Q Gnd is not at zero potential)} \quad (17)$$

If  $V_{o(min)}$  exceeds the breakdown voltage value of the selected Zener diodes, either  $V_{strg}$  or  $C_{INT}$  must be adjusted to maintain this inequality (see Equation (15)).

A number of engineering tradeoff considerations must be made in selecting RC components for the A/Z filter ( $R_4$ ,  $R_5$  and  $C_{strg}$ ). Some of these are covered in Appendix E. Various component values for different clock frequency ranges are presented in Table I, along with the recommended values for the integrator capacitor,  $C_{INT}$ .

TABLE I  
Auto/Zero Filter Values

$f_{IN}$ (kHz)	$C_{INT}$ ( $\mu$ F)	$C_{strg}$ ( $\mu$ F)	$R_4$ (K $\Omega$ )	$R_5$ (K $\Omega$ )
2 to 10	0.1	1.0	68	15
10 to 20	0.039	0.056	240	47
20 to 40	0.022	0.056	120	33
40 to 75	0.01	0.056	82	18

## APPLICATIONS

### Digital Voltmeters

The circuits shown in Figure 4 present the LD110/LD111 A/D converter set in typical  $\pm 2.000$  V digital voltmeter applications. The clock frequency of 24.5 kHz provides a sampling rate of 5 samples per second. Trimmer resistor  $R_6$  calibrates the DVM.  $R_1$  and  $R_2$  are metal film resistors.

The illustrated connection of the analog circuit grounds (Pins 2 and 7 of the LD111) and the digital circuit ground (Pin 12 of the LD110) is for schematic convenience only. The digital component grounds should be connected together and brought to a reference point such as the input voltage ground, and not directly to the pins of the LD111.

The use of a seven-segment LED for Digit 4 will allow the DVM to be employed up to the maximum count of 3100. The output of the BCD-to-seven-segment decoder will be erroneous during Digit 4 time, however, because under-range information is encoded on bit 4 during Digit 4 time. The bit 4 input of the decoder in Figure 4a (bit 4 is the most significant bit) should be clamped to ground during Digit 4 time to provide the correct Digit 4 readout, as in:

$$\text{Input D of decoder} = B_4 \cdot \bar{D}_4 \quad (18)$$

where  $B_n$  is the nth BCD data bit and  $D_n$  is the nth digit.

The display will blink at a rate equal to the sampling rate when the count exceeds 1999. If the grounding system is poor, erroneous readings will result for counts of 2000 and above.

The data output format is an interlaced scan of Digits, 1, 3, 2 and 4 with Digit 4 as the most significant digit. This permits the use of Sperry displays with clock frequencies of 25 kHz or less. All outputs are active high and TTL-compatible.

The overrange and underrange signals may be obtained by external logic, i.e.,

$$\text{MUX Underrange} = B_4 \cdot D_4 \text{ (5\% of full scale)} \quad (19)$$

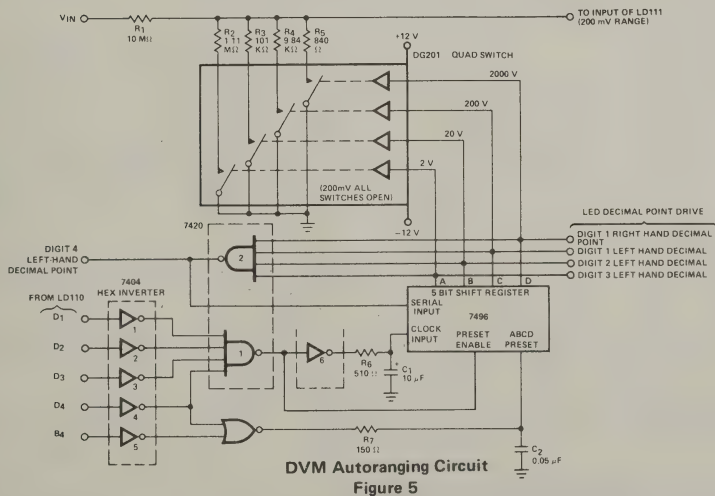
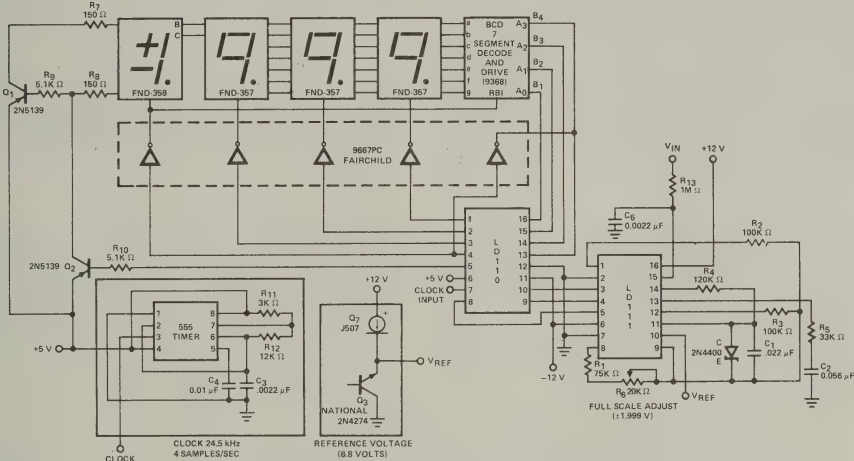
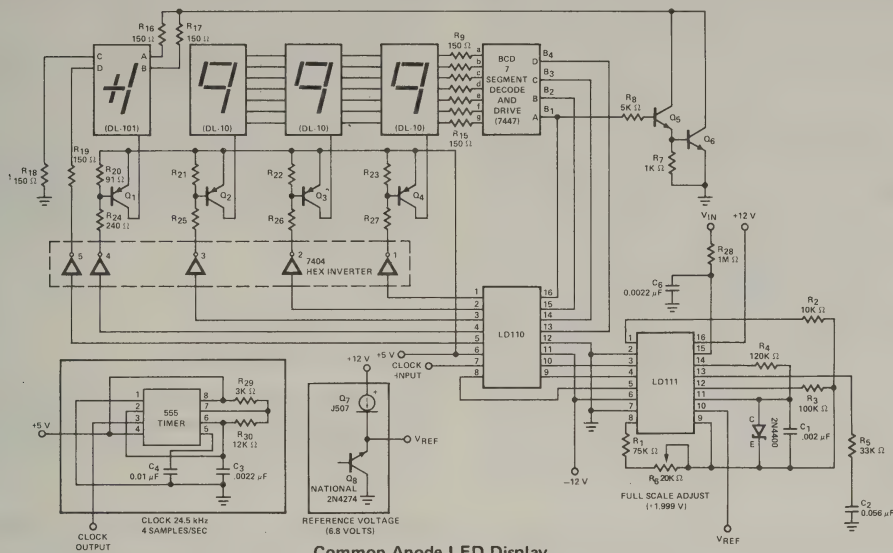
$$\text{MUX Overage} = \overline{D_1 + D_2 + D_3 + D_4} \text{ (100\% of full scale)} \quad (20)$$

### Autorangeing DVM

The circuit in Figure 5 shows how the decoded underrange and overrange signals can be used to make an automatic-ranging DVM. The circuit will cycle through five ranges (200 mV to 2,000 V), starting with the most sensitive range and proceeding through the less sensitive ranges until the proper operating range is attained.

When the cycle proceeds from the most sensitive to the least sensitive range, the proper range will be achieved for voltages which will provide a count between 1000 and 2000. If the cycle began at the least sensitive range, a voltage such as 15.0 V would be read on the 200 V range, since the count of 150 would not initiate an underrange signal to advance the circuit to a more sensitive range.

The two-input NOR gate decodes the underrange signal to preset the shift register with a "1" logic at each of the parallel bit outputs. A Siliconix DG201 quad SPST CMOS





analog transmission gate is employed in the circuit so that each of the four switches of the DG201 will be OFF when a logic "1" signal appears at the appropriate input.

Diodes  $D_1$  and  $D_2$  clamp the input of the LD111 processor at  $\pm 5$  V to prevent damage which could result from large input voltages. The presence of the overrange signal (Equation (20)), decoded by the combination of the five inverters and NAND gate 1, transfers the logic "0" signal which appears at NAND gate 2 into the shift register. Logic "0" appears at the A output of the shift register and turns on the DG201 switch which is associated with  $R_2$ , producing a voltage division of 10:1. The serial input of the shift register remains at logic "1" when any of the outputs are at logic "0", this insures that only one of the four DG201 switches is ON at a given time. The logic "0" signal is shifted through the register until the proper range is acquired. When the input voltage is removed the decoded underrange signal returns the shift register to the initial state.

The current-sinking capability of the shift register can be used to turn on the appropriate decimal point cathode of the LED display, with the only additional required component being a  $150\ \Omega$  current-limiting resistor. Inverters 1 through 4 can be used as inverters 1-4 of the DVM circuit shown in Figure 4. The filter  $R_6 C_1$  insures that there will be only one range change for each overrange signal, while the filter comprised of  $R_7 C_2$  eliminates an erroneous underrange signal which can occur if bit 4 of Digit 2 time overlaps into Digit 4 time.

The  $R_6 C_1$  and  $R_7 C_2$  filters are optimized for the 24.5 kHz clock frequency of the DVM circuit in Figure 4. Clock frequencies of less than 10 kHz or greater than 40 kHz may require the adjustment of  $C_1$  and  $C_2$ .

The ON resistance of the four switches in the DG201 quad transmission gate is typically  $160\ \Omega$  with  $\pm 12$  V supplies. This resistance has been considered in determining the values of range resistors  $R_2$ ,  $R_3$ ,  $R_4$  and  $R_5$ . Some trimming may, however, be necessary.

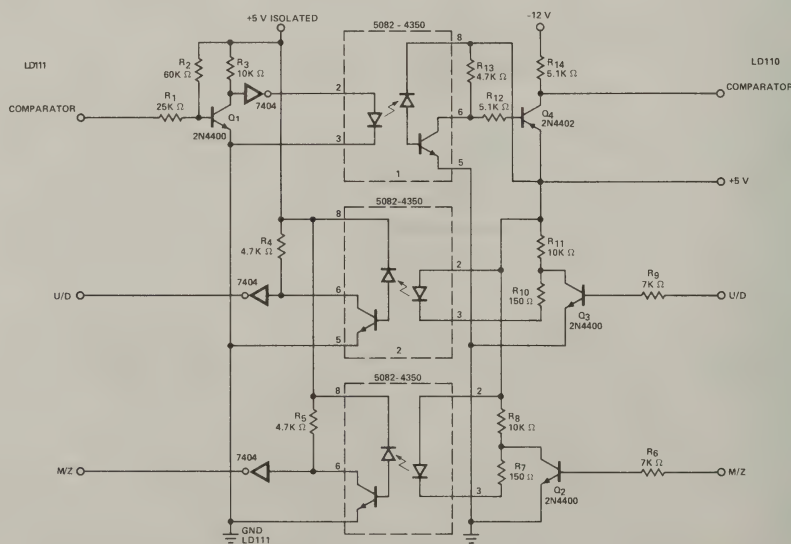
The input impedance is greater than  $10\ M\Omega$  on all ranges. Since the circuit changes range once every sampling period, the time required to attain a reading on the highest range is  $30720/f_{IN}$ .

### Isolated Analog Processor

The isolation circuit shown in Figure 6 provides a floating analog processor for measurement of off-ground signals such as those found in medical, nuclear, and process control instrumentation.

The three analog-to-digital interface signals (M/Z, U/D and comparator) are isolated via high-speed optical couplers with a 2,500 V insulation. Transistors  $Q_1$ ,  $Q_2$  and  $Q_3$  provide TTL level drive capability to interface the optical couplers with the LD110/LD111 system signals. The isolators in the M/Z and U/D channels are used in the non-inverting mode while the isolator in the comparator interface is used in the inverting mode. Transistor  $Q_4$  shift the TTL level signal to the MOS level required at the LD110 comparator input.

Although the isolators tend to shorten the pulse length of the LD110/LD111 system signals, the unique conversion technique of the system automatically compensates for this, and no additional adjustments are necessary.

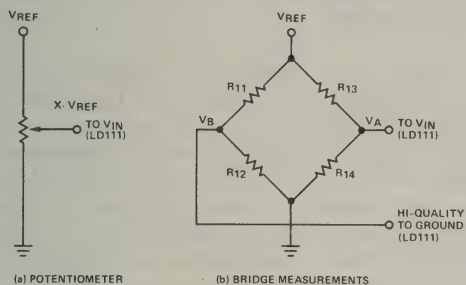


Optical Isolation Circuit  
Figure 6



## Ratio Measurements

Equation (6) shows that the LD110/LD111 A/D converter measures input voltage as a ratio: the count is proportional to the ratio of the input voltage and the reference voltage. This system conversion technique is ideally suited to the measurement of ratio. Ratio measurements using a reference voltage which is also the excitation voltage of the ratio device allows measurements to be independent of variations in the excitation voltage. Typical ratio-measuring circuits are shown.



Ratio Measurements  
Figure 7

The output of the potentiometer in Figure 7A (which can represent position, level, etc.) can be substituted in Equation (6) to demonstrate this capability:

$$\text{Count} = X V_{\text{REF}} \cdot \frac{R_1}{R_2} \cdot \frac{8192}{V_{\text{REF}}} = \frac{R_1}{R_2} \cdot 8192 X \quad (21)$$

Bridge transducer measurements, as shown in Figure 7B, can also be normalized to an external reference. The Hi-Q ground input of the LD111 functions as the inverting input of a difference amplifier to provide a count proportional to the difference of the two input voltages  $V_A$  and  $V_B$ .

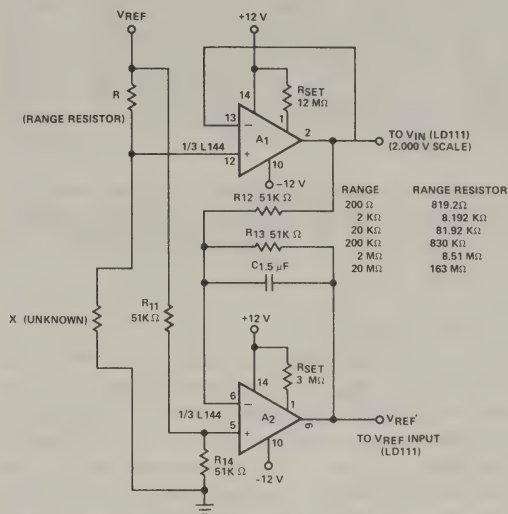
$$\begin{aligned} \text{Count} &= \frac{R_1}{R_2} \frac{8192}{V_{\text{REF}}} (V_A - V_B) \\ &= \frac{R_1}{R_2} 8192 \left( \frac{R_{14}}{R_{13} + R_{14}} - \frac{R_{12}}{R_{11} + R_{12}} \right) \quad (22) \end{aligned}$$

Ratio measurement techniques can also be extended to resistance measurement. The resistance-measuring circuit shown in Figure 8 will measure accurately to 20 M $\Omega$  when associated with a buffer amplifier ( $A_1$ ) having a low input bias current ( $I_{\text{IN}} < 30 \text{ nA}$ ). The circuit illustrated uses two of the three amplifiers contained in the Siliconix L144 micropower triple op amp.

This circuit exhibits a very high reference voltage rejection ratio, as shown by the following pertinent equations. (1)

$$V_{\text{IN}} = V_{\text{REF}} \left( \frac{X}{R + X} \right) \quad (23)$$

$$V_{\text{REF}}' = V_{\text{REF}} \left[ 1 - \frac{X}{R + X} \right] \frac{R_{14}}{R_{11}} \quad (24)$$



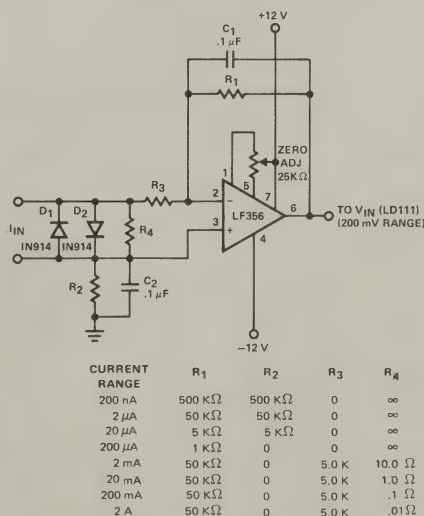
Resistance To Voltage Converter  
Figure 8

Substituting into Equation (6) yields

$$\text{Count} = 8192 \cdot \frac{X}{R} \cdot \frac{R_{11}}{R_{14}} \cdot \frac{R_1}{R_2} \quad (25)$$

## Current-To-Voltage Converter

A current-to-voltage converter featuring eight decades of current range is shown in Figure 9. The circuit is intended to be used with the 200.0 mV range of the DVM.



Current To Voltage Converter  
Figure 9

The arrangement actually comprises two different circuits, as examination of the table of resistance values in Figure 9 will show. The more sensitive ranges (up to 200  $\mu\text{A}$ ) use the amplifier in a differential mode to give an output equal to  $-2 I_{\text{IN}} R_1$ . This configuration effectively cancels the contribution of the input bias currents to the output voltage. (Since this error would be insignificant on the 200  $\mu\text{A}$  range,  $R_2$  is eliminated.)

The less sensitive ranges (2 mA to 2 A) use the amplifier in an inverting configuration to provide an output equal to  $-I_{IN} R_4 R_1/R_3$ .<sup>(2)</sup> Input protection is provided by diodes  $D_1$  and  $D_2$ .

## AC-To-DC Converter

When an AC-to-DC converter is designed using the LD110/LD111 converter set, the input impedance and input bias currents should approximate those of the LD111 input buffer amplifier. This is particularly true if the autoranging circuit of Figure 5 is used so that the same range resistors can be employed for both AC and DC measurements. The AC-to-DC converter shown in Figure 10 fulfills these requirements. The circuit includes a PMOS enhancement-mode

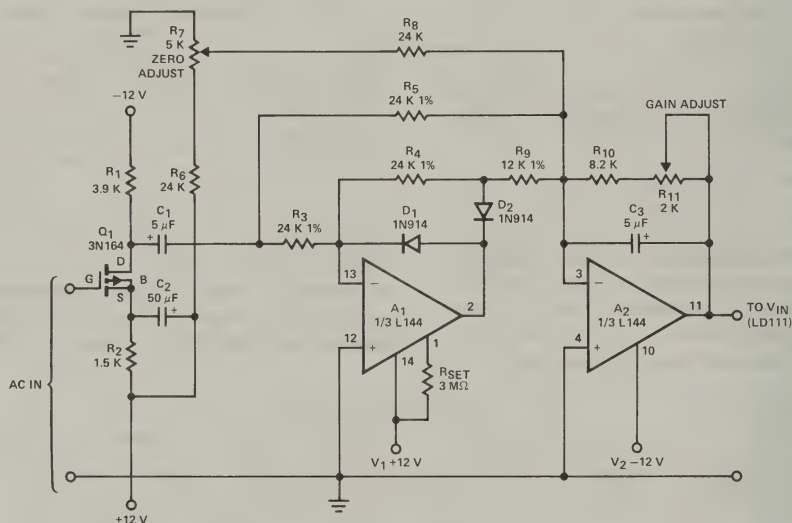
FET input buffer amplifier, coupled to a classical absolute value circuit which essentially eliminates the effect of the forward voltage drop across diodes  $D_1$  and  $D_2$ .

A filter removes the DC component of the rectified AC, which is then scaled to RMS. The output is linear from 40 Hz to 10 kHz or higher.

## Digital Frequency Meter

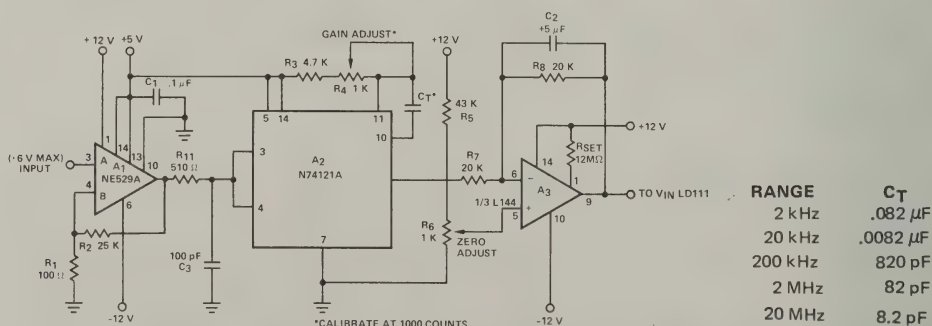
A digital frequency meter can be fashioned by using the circuit shown in Figure 11 with the basic 2-volt DVM circuit shown in Figure 4.

The circuit converts frequency to voltage by taking the average DC value of the pulses from the 74121 monostable multivibrator. The one-shot is triggered by the positive-going AC signal at the input of the 529 comparator. The amplifier acts as a DC filter, and also provides zeroing. This circuit will maintain an accuracy of 2% over 5 decades of range. The input signal to the comparator should be greater than 0.1 volt peak-to-peak, and less than 12 volts peak-to-peak for proper operation.



### AC to DC Converter

#### Figure 10

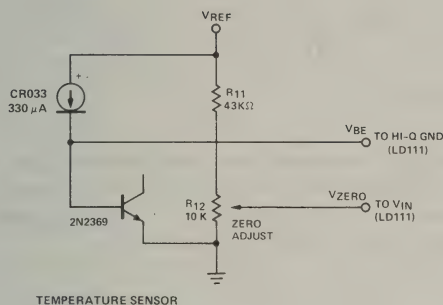


### Frequency To Voltage Converter

Figure 11

## Digital Thermometer

A digital thermometer can be constructed by using the change in forward voltage drop across a PN junction as the temperature-sensitive element in the circuit. This change is typically  $-2.3 \text{ mV}/^\circ\text{C}$ . The circuit shown in Figure 12 has the base-emitter junction of a bipolar transistor biased with a  $470 \mu\text{A}$  current source.



NOTE:  
THE DVM SHOWN IN FIGURE 4 MUST BE CHANGED  
IN THE FOLLOWING WAYS FOR THIS APPLICATION

1.  $R_3 = 51 \text{ K}\Omega$
2.  $R_2 = 23 \text{ K}\Omega$  (CENTIGRADE SCALE)  
 $11 \text{ K}\Omega$  (FAHRENHEIT SCALE)
3. HI-QUALITY GND NO LONGER CONNECTED TO  
GROUND

Temperature To Voltage Converter  
Figure 12

The junction voltage  $V_{BE}$  is applied to the input buffer amplifier of the analog processor which functions as a differential amplifier. The buffer resistor  $R_2$  is scaled to give a count proportional to temperature as shown by the following equations:

$$\text{Count} = \frac{R_1}{R_2} \frac{8192}{V_{REF}} [V_{ZERO} - V_{BE}(T)] \quad (26)$$

AND SO:

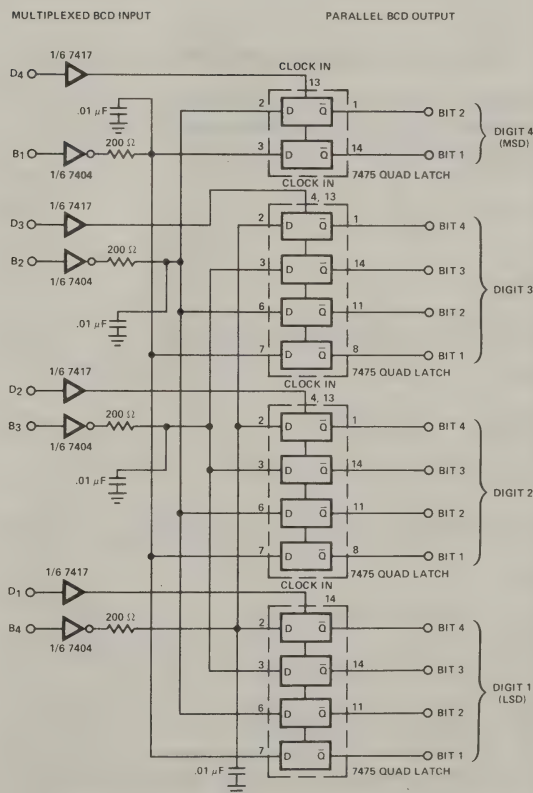
$$\text{Count} = 1000 A [V_{ZERO} - V_{BE}(T)] \quad (27)$$

Gain  $A$  must be approximately 5 for the Centigrade scale and 9 for the Farenheit scale.

## Multiplexed BCD To Parallel BCD Converter

Although the multiplexed BCD output of the LD110/LD111 A/D converter set is useful for digital displays, there are applications (such as printer inputs) in which the BCD data for all four digits should be available in a parallel format. The multiplexed BCD-to-parallel-BCD converter shown in Figure 13 will provide the proper interface for such applications.

The converter consists of 4 quad bistable latches activated in the proper sequence by the digit strobe output of the LD110. The complemented outputs ( $\bar{Q}$ ) of the quad latch set will reflect the state of the bit outputs when the digit strobe goes high, and will maintain this state when the digit strobe goes low. The latches will be updated with the next digit strobe. This parallel BCD output will not then be affected by the blinking-off of the digit strobes when the count exceeds 1999 (overrange), and can be used to drive a non-blinking display up to a full scale of 3000 counts. The parallel BCD output can be put in a "hold" state by latching all digit strobes to ground to prevent the updating of the latches.



Multiplexed BCD To Parallel BCD Converter  
Figure 13



## CONCLUSIONS

The LD110/LD111 A/D converter integrated circuit set lends itself to a wide range of applications in which analog information is desired in digital format. High accuracy and long term stability combined with a minimum of external circuitry and calibration requirements make this converter set a superior choice for any application. The circuit examples presented are intended to be of general interest, and do not touch upon the wide variety of more specialized applications.

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- (3) J. D'Azzo and C. Houpis, Feedback Control System Analysis and Synthesis, McGraw-Hill Co. New York, 1960, pp. 81-83.

APPENDIX A: ERROR ANALYSIS FOR  $V_{REF}$ 

Equation (6) will be used to derive the count error to be expected for changes in the reference voltage  $V_{REF}$  due to temperature changes or load regulation.

$$\text{Count}' = V_{IN} \frac{R_1}{R_2} \frac{8192}{V_{REF}'} \quad (6)$$

WHERE:

$$\text{Count}' = \text{Count (Ideal)} + \Delta \text{Count (Error)} \quad (28)$$

AND

$$V_{REF}' = V_{REF} + \Delta V_{REF} \quad (29)$$

Substituting (28) and (29) into (6) yields

$$\text{Count} + \Delta \text{Count} = V_{IN} \frac{R_1}{R_2} \frac{8192}{(V_{REF} + \Delta V_{REF})} \quad (30)$$

OR:

$$\begin{aligned} \text{Count} \cdot V_{REF} + \text{Count} \cdot \Delta V_{REF} + \Delta \text{Count} \cdot V_{REF} \\ + \Delta \text{Count} \cdot \Delta V_{REF} = V_{IN} \frac{R_1}{R_2} 8192 \end{aligned} \quad (31)$$

The quantity  $\Delta \text{Count} \cdot \Delta V_{REF}$  is very small in relation to the other factors and can be eliminated. The product  $\text{Count} \cdot V_{REF}$  is equal to  $V_{IN} \frac{R_1}{R_2} 8192$  and so these factors can be eliminated from both sides of equation (31) leaving

$$\text{Count} \cdot \Delta V_{REF} + \Delta \text{Count} \cdot V_{REF} = 0 \quad (32)$$

THEREFORE:

$$\Delta \text{Count} = - \text{Count} \frac{\Delta V_{REF}}{V_{REF}} \quad (33)$$

This can be related to  $V_{IN}$  by noting that the full-scale count is 2000, thus:

$$\Delta \text{Count} = -2000 \frac{V_{IN}}{V_{IN} (F.S.)} \frac{\Delta V_{REF}}{V_{REF}} \quad (34)$$

The reference supply shown in Figure 4 has a typical temperature coefficient of  $\pm 20 \text{ ppm}/^\circ\text{C}$ . Therefore the reference voltage would change by 0.1% for an increase in temperature of  $50^\circ\text{C}$  ( $20^\circ\text{C}$  to  $70^\circ\text{C}$ ). The maximum error will occur when  $V_{IN}$  equals the full scale voltage  $V_{IN} (F.S.)$  as shown below.

$$\Delta \text{Count} = -2000 \frac{V_{IN} (F.S.)}{V_{IN} (F.S.)} (.001) \quad (35)$$

$$\Delta \text{Count} = -2 \quad (36)$$

If no other effects were present, the DVM in Figure 4 will show a decrease of 2 in the count for a  $50^\circ\text{C}$  increase in temperature, if the reference Zener diode has a positive  $20 \text{ ppm}/^\circ\text{C}$  temperature coefficient.

APPENDIX B: TEMPERATURE EFFECT OF  $R_{DS(on)}$  (U/D SWITCH)

The analysis of the readout error caused by a change in the  $R_{DS(on)}$  of the U/D switch will proceed along similar logic as that of Appendix A. Again we look at Equation (6).

$$\text{Count}' = V_{IN} \frac{R_1'}{R_2} \frac{8192}{V_{REF}} \quad (6)$$

WHERE

$$\text{Count}' = \text{Count (Ideal)} + \Delta \text{Count (Error)} \quad (28)$$

AND

$$R_1' = R_1 (\text{Ideal}) + \Delta R_1 \quad (37)$$

Substituting (28) and (37) into (6) yields,

$$\text{Count} + \Delta \text{Count} = V_{IN} \frac{R_1}{R_2} \frac{8192}{V_{REF}} + V_{IN} \frac{\Delta R_1}{R_2} \frac{8192}{V_{REF}} \quad (38)$$

Eliminating Equation (6) from (38) gives the change in count ( $\Delta \text{Count}$ ).

$$\Delta \text{Count} = V_{IN} \frac{\Delta R_1}{R_2} \frac{8192}{V_{REF}} \quad (39)$$



BUT:

$$V_{REF} = V_{IN} \frac{R_1}{R_2} \frac{8192}{\text{Count}} \quad (40)$$

so that by substituting (40) into (39) yields

$$\Delta \text{Count} = \frac{\Delta R_1}{R_1} \text{Count} \quad (41)$$

or by relating the count to the input voltage  $V_{IN}$  we see that:

$$\Delta \text{Count} = 2000 \frac{V_{IN}}{V_{IN} \text{ (F.S.)}} \frac{\Delta R_1}{R_1} \quad (42)$$

We can now examine how the temperature dependency of  $R_{DS(on)}$  (U/D Switch) will affect the accuracy of the DVM application circuit of Figure 4. Using Figure 3, it can be seen that  $R_{DS(on)}$  will increase by  $100 \Omega$  when the ambient temperature changes by about  $50^\circ\text{C}$  ( $V_{REF} = 6.8$  volts). The maximum error ( $V_{IN} = V_{IN} \text{ (F.S.)}$ ) will be:

$$\Delta \text{Count} = \frac{100 \Omega}{83 \text{ K}\Omega} 2000 = 2.41 \quad (43)$$

The net count error will then be due to the sum of the error associated with  $V_{REF}$  and the error due to the change is  $R_{DS(ON)}$  which is:

$$\text{Net Count Error} = \Delta \text{Count} (V_{REF}) + \Delta \text{Count} (R_1) \quad (44)$$

$$\text{Net Count Error} = -2 + 2.41 = .41 \text{ counts} \quad (45)$$

If the reference resistor  $R_1$  and the input resistor  $R_2$  have the same temperature coefficients, the temperature effects of these resistors will be balanced out.

### APPENDIX C: PROPER SELECTION OF THE INTEGRATOR CAPACITOR $C_{INT}$

In order to maintain good accuracy, the integrator output  $V_O$  should not be allowed to deviate from  $V_{strg}$  by more than 0.75 volts. The maximum deviation from  $V_{strg}$  will occur when the maximum input current  $\frac{V_{IN} \text{ (F.S.)}}{R_2}$  is of

the same sense as the reference current. These considerations are shown in the following mathematical expressions:

$$|\Delta V_O| = \frac{1}{C_{INT}} \int_0^{7/f_{IN}} \left( \frac{V_{IN} \text{ (F.S.)}}{R_2} + \frac{V_{REF}}{2R_1} \right) dt \quad (46)$$

SO

$$|\Delta V_O| = \frac{7}{C_{INT} f_{IN}} \left[ \frac{V_{REF}}{2R_1} + \frac{V_{IN} \text{ (F.S.)}}{R_2} \right] \quad (47)$$

BUT:

$$R_1 = \frac{2000 V_{REF} R_2}{8192 V_{IN} \text{ (F.S.)}} \quad \text{See Eq. (6)} \quad (48)$$

Substituting (48) into (47) yields

$$|\Delta V_O| = \frac{7}{C_{INT} f_{IN}} \left[ \frac{2.048 V_{IN} \text{ (F.S.)}}{R_2} + \frac{V_{IN} \text{ (F.S.)}}{R_2} \right] \quad (49)$$

AND

$$|\Delta V_O| = \frac{21.336 V_{IN} \text{ (F.S.)}}{R_2 C_{INT} f_{IN}} \quad (50)$$

Setting this absolute deviation equal to 0.75 volts gives

$$C_{INT} = \frac{28.45 V_{IN} \text{ (F.S.)}}{R_2 f_{IN}} \quad (51)$$

For the application circuit of Figure 4:

$$R_2 = 100 \text{ K}\Omega$$

$$f_{IN} = 24.5 \text{ kHz}$$

$$V_{IN} \text{ (F.S.)} = 2.000 \text{ volts}$$

From equation (51) then:

$$C_{INT} = 0.0232 \mu\text{F} \quad (52)$$

and we choose the closest standard value which is  $0.022 \mu\text{F}$ .

### APPENDIX D: ERROR DUE TO $C_{INT}$ LEAKAGE

In order to determine how much leakage from integrator capacitor  $C_{INT}$  is tolerable we must first find the relationship between read-out error and leakage current  $I_L$ . From Equation (1) it can be seen that the charge  $Q$  proportional to 1 count is:

$$Q \text{ per count} = \frac{-V_{REF}}{2 R_1 f_{IN}} \quad (53)$$

Therefore, to maintain an error of less than 1 count, the net charge leaked from  $C_{INT}$  during the measure interval must be less than the charge associated with 1 count.

$$I_L \Delta t_{\text{measure}} < \frac{V_{REF}}{2 R_1 f_{IN}} \quad (54)$$

OR

$$\frac{4096 I_L}{f_{IN}} < \frac{V_{REF}}{2 R_1 f_{IN}} \quad (55)$$

THUS

$$I_L < \frac{V_{REF}}{8192 R_1} \quad (56)$$

Given the values for the application circuit of Figure 4,

$$R_1 = 83 \text{ K (after trimming)}$$

$$V_{REF} = 6.8 \text{ volts}$$

THEN:

$$I_L < 10 \text{ nA to have less than 1 count error}$$

## APPENDIX E: RC TIME CONSTANTS FOR AZ FILTER

The component values for the RC time constants of the AZ Filter ( $R_4$ ,  $R_5$  and  $C_{STRG}$ ) are derived from a consideration of the following transfer functions:

1. The low pass filter composed of  $R_4$ ,  $R_5$   $C_{strg}$  and the AZ amplifier has a transfer function  $G_1(S)$

$$G_1(S) = \frac{V_{AZ}}{V_O} = \frac{R_5}{R_4 + R_5} \frac{S + 1/R_5 C_{strg}}{S + 1/C_{strg} (R_4 + R_5)} \quad (57)$$

which is of the form

$$G_1(S) = \alpha \frac{S + 2\pi f_2}{S + 2\pi f_1} \quad (58)$$

where  $\alpha$  is the high frequency gain of this filter and  $f_1$  and  $f_2$  are the pole and zero frequencies respectively.

2. The closed-loop system composed of the integrator and AZ amplifier has the transfer function  $G_2(S)$  shown below:

$$G_2(S) = \frac{V_O}{V_{IN}} = \quad (59)$$

$$S C_{STRG} (R_4 + R_5) + 1$$

$$S^2 R_3 C_{INT} C_{strg} (R_4 + R_5) + S (R_3 C_{INT} + R_5 C_{strg}) + 1$$

which is of the form

$$G_2(S) = \frac{S T_1 + 1}{\frac{1}{\omega_n^2} S^2 + \frac{2\zeta}{\omega_n} S + 1} \quad (60)$$

SO THAT

$$\omega_n^2 = \frac{1}{R_3 C_{INT} C_{strg} (R_4 + R_5)} \quad (61)$$

AND

$$4\zeta^2 = \frac{R_5^2 C_{strg}}{R_3 C_{INT} (R_4 + R_5)} + \frac{2R_5}{R_4 + R_5} + \frac{R_3 C_{INT}}{C_{strg} (R_4 + R_5)} \quad (62)$$

where  $\omega_n$  is  $2\pi$  times the natural frequency and  $\zeta$  is the system damping factor.

With these equations,  $R_4$  and  $R_5$  can be determined.  $C_{INT}$  should already be chosen (see Appendix C) and  $C_{strg}$  can be somewhat arbitrarily chosen (.1  $\mu F$  is a good choice to keep  $R_4$  and  $R_5$  at useful resistance values). The following procedure evolved from a desire to decrease the high frequency gain  $\alpha$  of the low pass filter while maintaining a well damped Auto-Zero system. The procedure is as follows:

- a) From Equations (57) and (58) it can be found that:

$$f_1 = \frac{1}{2\pi C_{strg} (R_4 + R_5)} \quad (63)$$

The total resistance ( $R_4 + R_5$ ) can be solved for by setting  $f_1$  equal to 2 times the sampling rate.

- b) Since the sum  $R_4 + R_5$  is known,  $R_5$  can be found by setting the damping factor equal to 0.4 and solving for  $R_5$  using Equation (62).

- c)  $R_4$  can then be found now that  $R_5$  is known.

These AZ filter component values will be valid if:<sup>3</sup>

$$\frac{2048}{f_{IN}} \zeta \omega_n \geq 5 \quad (64)$$

This assures that  $V_{strg}$  settles properly during the auto-zero period. If the values determined for  $R_4$  and  $R_5$  do not meet this criteria, a higher value of damping factor should be chosen and the determination of  $R_5$ , as delineated in step b, should be repeated.

**Replace LD111 with LD111A**  
*for New Designs*

1/8 A. SLO-BLO

110

220

8

7

6

5

SIGNAL  
DPC 24-450

IN4002 (X 4)

510  $\Omega$   $\frac{1}{4}$  W

IN962

39  $\Omega$  2 W

2N1711\*

560  $\Omega$   $\frac{1}{2}$  W

1,000  $\mu$ F 25 V

500  $\mu$ F 25 V

1,000  $\mu$ F 25 V

IN752

IN962

1 K  $\Omega$

100  $\Omega$   $\frac{1}{2}$  W

2N5139

+12 V

0.01  $\mu$ F

+5 V

GND

-12 V

\*HEAT SINK REQUIRED

The circuit diagram illustrates a digital-to-analog converter (DAC) system. It consists of several key components and their interconnections:

- Input and Decoding:** A 4-bit digital input (pins 14, 13, 12, 11) is fed into a 9368 4-bit counter. The counter's outputs (pins 8, 11, 7, 10, 9, 13, 12, 14) are connected to three DL-701 and DL-702 decoders. These decoders drive three 7416 comparators (pins 4, 6, 2, 12, 10, 8, 13, 11, 9).
- Reference and Comparison:** A 555 timer (pins 1, 2, 3, 4, 5, 8, 7, 6, 5) is configured as a voltage divider, providing a reference voltage to the comparators. The comparators' outputs (pins 1, 2, 3, 4, 5, 6, 7, 8, 9, 10, 11, 12, 13, 14, 15, 16) are connected to the LD110 and LD111 comparators.
- Analog Output and Trimming:** The LD110 and LD111 comparators (pins 1, 2, 3, 4, 5, 6, 7, 8, 9, 10, 11, 12, 13, 14, 15, 16) are connected to an optional voltage divider (pins 10 MΩ, 1 MΩ, 100 KΩ, 10 KΩ) and a 1.11 KΩ resistor. The output is connected to the ANALOG INPUT (pin 1) and the V(IN) LOW (pin 2) of the LD110 and LD111 comparators. A 0.0022 μF capacitor is connected to the V(IN) LOW pin.
- Power and Timing:** The circuit is powered by +5V, -12V, and +12V rails. A 0.0022 μF capacitor is connected to the +5V rail, and a 0.01 μF capacitor is connected to the -12V rail. A 4-40 pF trimmer (ZERO ADJ., OPTIONAL) is connected to the +12V rail. A 0.056 μF capacitor is connected to the -12V rail.

\*2N4400 not required when using LD111A.



## METAL PATTERN FOR DVM BOARD

(refer to last page of design aid for 1:1 P.C. pattern)

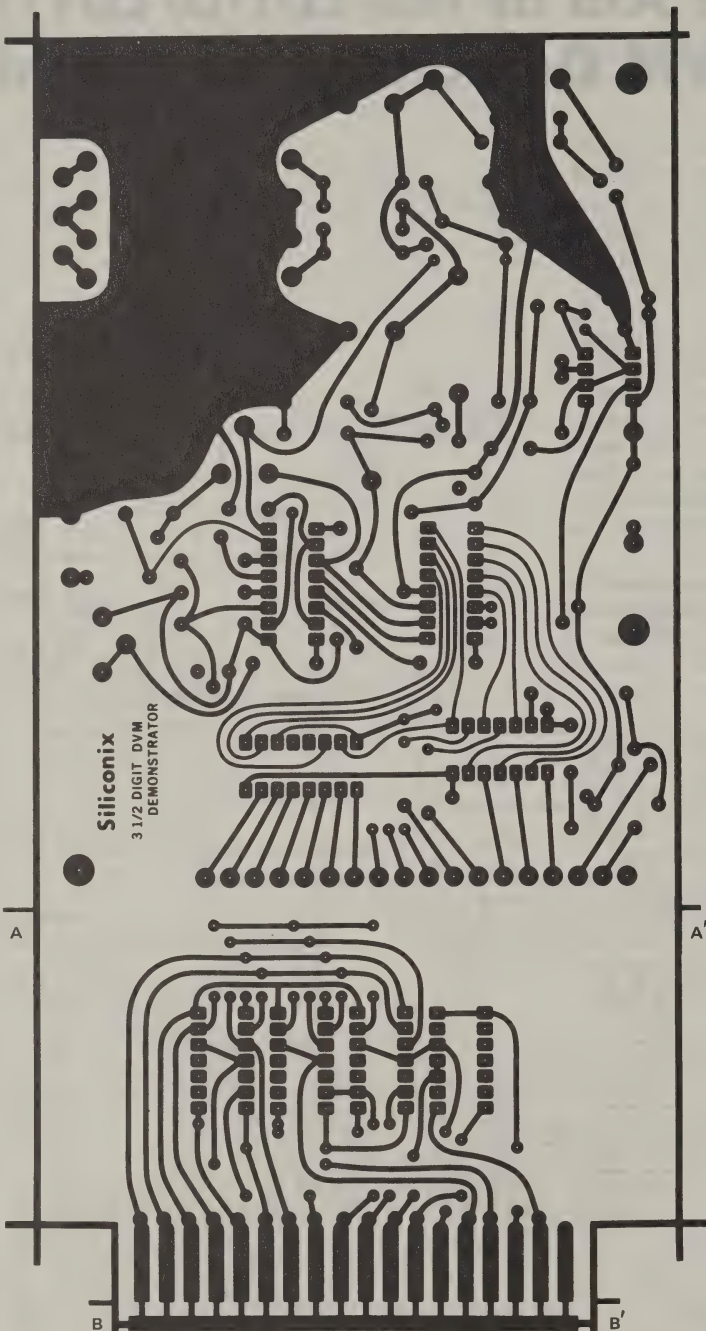
Replace LD111 with LD111A  
for New Designs

## FABRICATION HINTS

1. All holes require a #60 drill except for the following holes which require a #54 drill.
  - a) Transformer
  - b) AC input
  - c) Power Supply filter capacitors
  - d)  $39\ \Omega$  Resistor in Power Supply
  - e) Trimmer Resistor (10K)
  - f) Trimmer Capacitor
  - g) Edge Connector (labeled A thru Q)
  - h)  $V_{IN}$  (Hi and Lo)

The location of these holes may be determined from the component placement diagram and the adjacent metal pattern.

2. Shear board along lines A-A' and B-B'.



CIRCUIT BOARD  
(Bottom View)

LED DISPLAY BOARD  
(Back View)



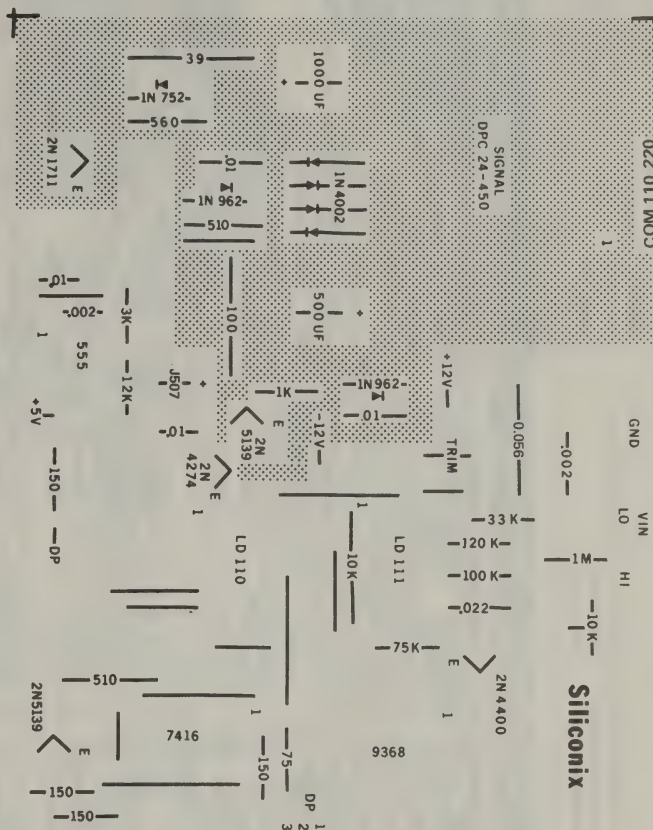
### COMPONENT PLACEMENT DIAGRAM

(refer to last page of design aid for 1:1 P.C. pattern)

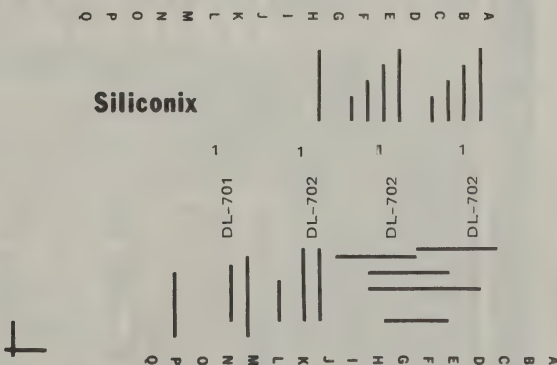
## INSTALLATION HINTS

1. A solid line between two holes requires a jumper wire.
2. The dotted area denotes the optional power supply. If bench power is to be used, it can be attached to the pads marked +12 V, -12 V and +5 V.
3. AC line input to "COM" and "110" for 110 VAC 50-60 Hz and to "COM" and "220" for 220 VAC 50-60 Hz.
4. Pin 1 of the transformer should be aligned with hole marked "1".
5. Filter Caps, whether axial or radial lead type should be upright.
6. Anode of E507 denoted by flat spot.
7. 2N1711 requires a heat sink.
8. Display board can be directly wired to main board if desired — thus eliminating connector.
9. Use Molex strip sockets for LD110/LD111.
10. If the readout has a slight negative offset with a grounded input, an optional trim capacitor can be added to the board (where TRIM is marked). This can be a 4-40 pF trimmer or a fixed capacitor as needed to zero the reading.

CIRCUIT BOARD  
(Top View)



**LED DISPLAY BOARD**  
(Front View)



**CAUTION!**

The AC line voltages associated with this board can be fatal to human life. Proper precautions for operating this instrument must be observed by the user. Siliconix assumes no liability for unsafe operation.

BASIC DVM Electrical Parts List			OPTIONAL POWER SUPPLY Electrical Parts List		
Quantity Required	Description	Recommended Manufacturer And Part Number	Quantity Required	Description	Recommended Manufacturer And Part Number
1	Analog IC	Siliconix LD111	1	Supply Transformer	*Signal or EWC DPC24-450
1	Digital IC	Siliconix LD110	1	PNP Transistor	Fairchild 2N5139
1	BCD to 7 Segment Decoder/Driver	Fairchild 9368DC	1	NPN Transistor	Motorola 2N1711
1	Timer IC	Signetics NE555V	1	5.6 Volt Zener Diode	Motorola IN752
1	Hex Buffer/Inverter	National DM7416N	2	11 Volt Zener Diode	Motorola IN962
1	±1 Overflow LED Display	Litronix DL-701	4	100 Volt Rectifier Diode	Motorola IN4002
3	7 Segment LED Display	Litronix DL-702	1	1,000 $\mu$ F 25 Volt Electrolytic	Sprague 503D108G025EU
1	NPN Transistor	Motorola 2N4400	1	500 $\mu$ F 25 Volt Electrolytic	Sprague 503D477G025EK
1	NPN Transistor	National 2N4274	3	0.01 $\mu$ F Ceramic Cap.	
1	PNP Transistor	Fairchild 2N5139	1	100 $\Omega$ 10% Resistor	Allen-Bradley
1	Current Limiting Diode	Siliconix J507	1	39 $\Omega$ 2 watt 10% Resistor	Allen-Bradley
1	0.022 $\mu$ F 80 Volt Mylar Cap.	Sprague 192P2239R8	1	510 $\Omega$ 1/4 watt 5% Resistor	Allen-Bradley
1	0.056 $\mu$ F 80 Volt Mylar Cap.	Sprague 192P5639R8	1	560 $\Omega$ 1/2 watt 10% Resistor	Allen-Bradley
1	0.0022 Ceramic Cap.		1	1 K $\Omega$ 1/4 watt 5% Resistor	Allen-Bradley
1	4-40 pF Trimmer Cap. (Optional)	Johanson 9304	1	Power Cord, 2 Wire	Little-fuse 357-001
1	0.01 $\mu$ F Ceramic Cap.		1	Fuse Holder	
1	10K Potentiometer	CTS X201R103B	1	1/8 Amp Slo-Blo Fuse	Wakefield 205-CB
1	75 $\Omega$ 1/4 watt 5% Resistor	Allen-Bradley	1	Heat Sink (for 2N1711 transistor)	
4	150 $\Omega$ 1/4 watt 5% Resistor	Allen-Bradley	OPTIONAL 5 RANGE VOLTAGE DIVIDER		
1	510 $\Omega$ 1/4 watt 5% Resistor	Allen-Bradley	1	10 M $\Omega$ 0.1% 1/2 watt Resistor	The divider resistors should be mounted on the rotary range switch.
1	3 K $\Omega$ 1/4 watt 5% Resistor	Allen-Bradley	1	1 M $\Omega$ 0.1% 1/4 watt Resistor	
1	10 K $\Omega$ 1/4 watt 5% Resistor	Allen-Bradley	1	100 K $\Omega$ 0.1% 1/4 watt Resistor	
1	12 K $\Omega$ 1/4 watt 5% Resistor	Allen-Bradley	1	100 K $\Omega$ 0.1% 1/4 watt Resistor	
1	33 K $\Omega$ 1/4 watt 5% Resistor	Allen-Bradley	1	1.1 K $\Omega$ 0.1% 1/4 watt Resistor	
1	75 K $\Omega$ 1/4 watt 5% Resistor	Allen-Bradley	1	2 Pole 5 Position Rotary Switch	Centralab PA-3 and 30° Index
1	100 K $\Omega$ 1/4 watt 5% Resistor	Allen-Bradley	2	Banana Jacks	
1	120 K $\Omega$ 1/4 watt 5% Resistor	Allen-Bradley	*This transformer may be ordered from:		
1	1 M $\Omega$ 1/4 watt 5% Resistor	Allen-Bradley	Signal Transformer Co.		
32	Socket Pins (use for LD110 and LD111)	Molex	1 Julius Street		
1	18 pin Edge Connector	Amphenol 143-018-03	Brooklyn, NY 11212		
			(only direct from factory)		
			EWC, inc (#DPC-24-450B19)		
			725 Federal Avenue		
			Kenilworth, NJ 07033		
			(available through factory or West coast distributors)		

C' Metal Pattern

Scale 1:1

Circuit Board  
(Bottom View)

LD110/111 3 1/2 Digit DVM Demonstrator

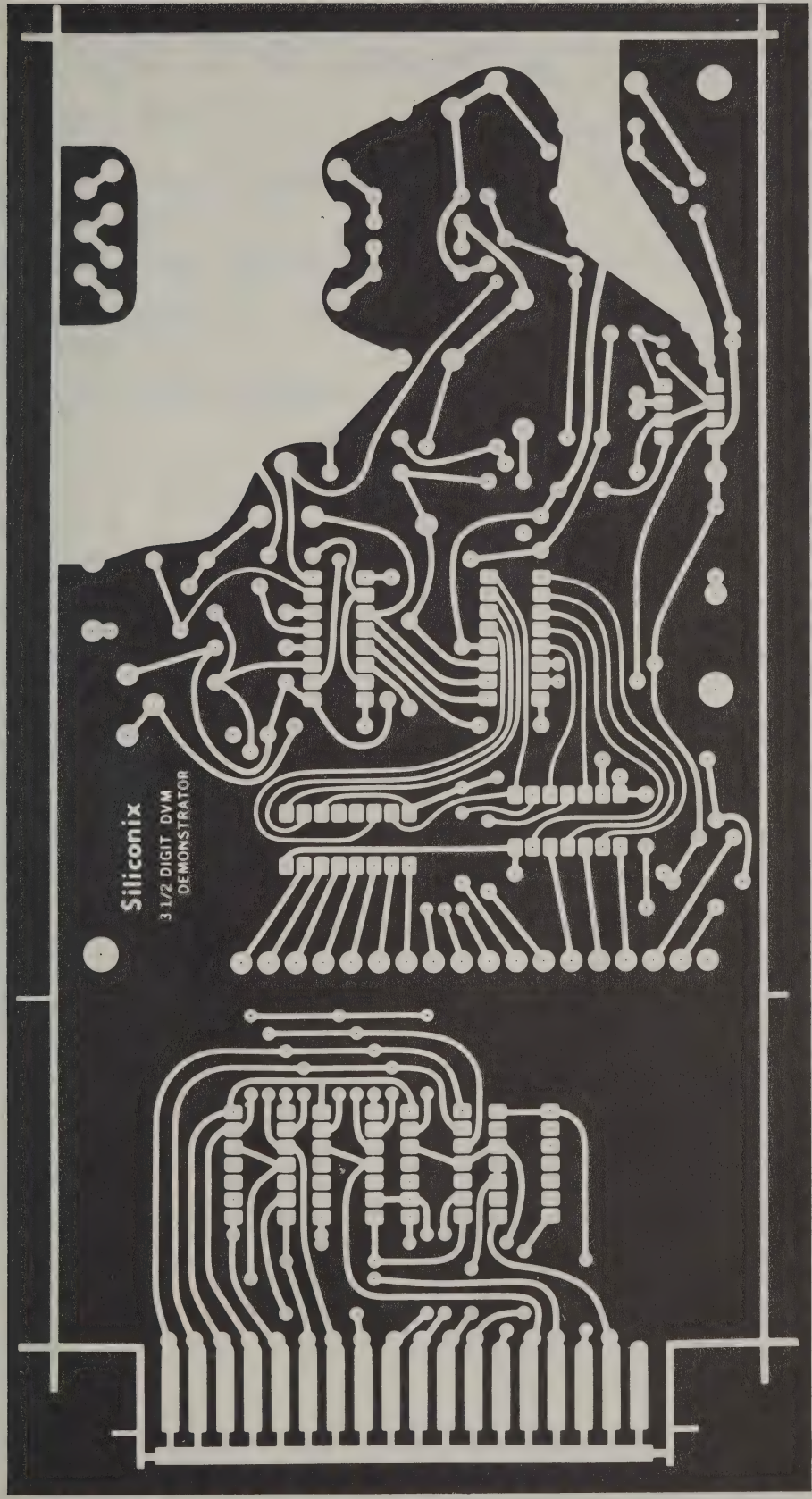
A' LED Display Board  
(Bottom View)

B'

C

A

B

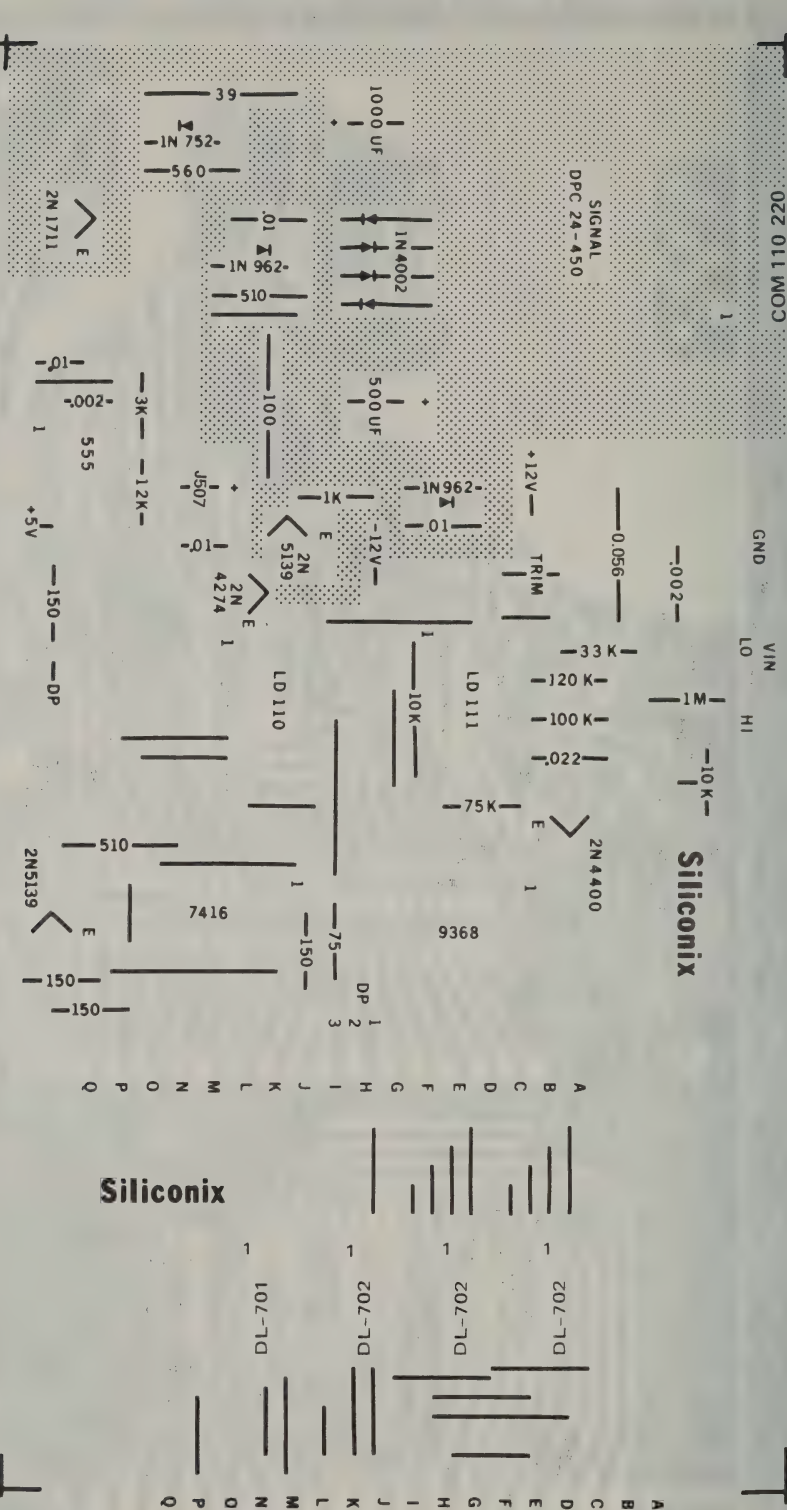


Siliconix



Circuit Board  
(Top View)

D Display Board  
(Top View)





# 4 1/2 Digit A/D Converter Set

designed for . . .

- High Accuracy Digital Voltmeters, Panel Meters
- Digital Scales, Thermometers
- Microprocessor Data Acquisition Systems
- Scientific Instrumentation

Replace LD121 with LD121A  
for New Designs

## DESCRIPTION

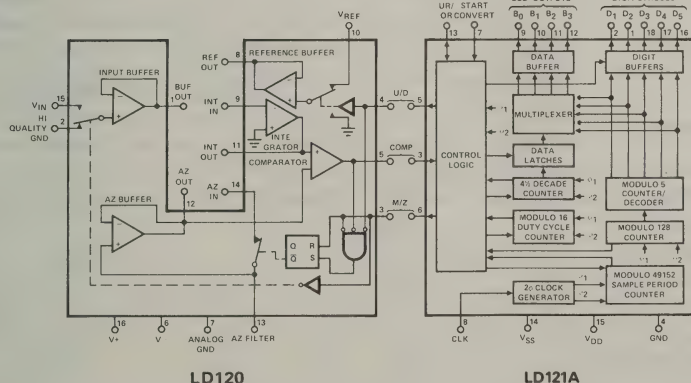
The LD122/LD121A 4 1/2 digit A/D system uses Siliconix's "Quantized Feedback" conversion technique. Intrinsic features of this system are Auto-Polarity, Auto-Zero and ratiometric operation. No critical components are required except for a stable voltage reference and a low noise op amp. The technique offers superior linearity, normal mode rejection, and stability due to the simultaneous integration of the unknown input and the reference voltages. Unlike other conversion techniques, the integrator output voltage never represents more than 100 counts, thus critical, high resolution performance is not required of either the integrator or comparator.

The LD120 analog processor is fabricated with a unique combined PMOS/Bipolar process. It contains all the necessary amplifiers, MOSFET switches, and switch driver circuits for the system. The reference voltage input is fully buffered on the LD120 to eliminate the reference switch resistance as a source of error. All the amplifiers are internally compensated. The LD120 directly interfaces the LD121A digital processor with no additional active components required.

The LD121A synchronous processor contains all the digital circuitry for the quantized feedback system. Device outputs supply two overrange signals, underrange, sign and 4 1/2 digits of multiplexed BCD data. (All outputs are TTL compatible). Overage is also indicated by blinking digit strobes above 20,000 counts. An input is provided to inhibit this feature at user option. Microprocessor controlled operation is simplified by a start conversion input that allows conversion-on-command.

Both devices are supplied in space saving 300 mil dual-in-line plastic packages. The LD120 has 16 pins and the LD121A has 18 pins.

## FUNCTIONAL BLOCK DIAGRAM



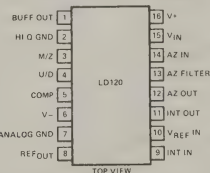
SWITCH STATES ARE FOR A LOGIC "0" AT U/D AND M/Z INPUTS.

## BENEFITS

- 0.005%  $\pm 1$  Count Accuracy Ensures High System Performance
- Two Ranges,  $\pm 2.0000$  V or  $\pm 200.0$  mV, With Single Resistor Change
- 28,672 Count Maximum For 42.5% Over-range
- Sample Rate From One to Five/Second
- Auto-Zero Cycle Nulls Out Internal and External Amplifier Offsets
- Auto-Polarity Operation with One Reference
- Multiplexed BCD Output For Easy Interface To Displays
- Two Overage Outputs, Underrange Output, Blink Inhibit, and Convert-On-Command Capabilities Allow Easy Interface to External Circuitry and Microprocessors

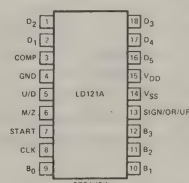
## PIN CONFIGURATIONS

### Dual-In-Line Package



ORDER NUMBER LD120CJ  
SEE PACKAGE 8

### Dual-In-Line Package



ORDER NUMBER LD121ACJ  
SEE PACKAGE 19

## ABSOLUTE MAXIMUM RATINGS

$V_{IN}$ (Pin 15, 2 LD120) . . . . .	$V- < V_{IN} < V+$
$I_{INPUT}$ (LD120) . . . . .	$\pm 1$ mA
$V+ - V-$ (LD120) . . . . .	32 V
$V_{SS} - V_{DD}$ (LD121A) . . . . .	20 V
Any Pin (LD121A) . . . . .	$V_{DD}$ to $V_{SS} \pm 0.3$
$V_{REF}$ . . . . .	$V+$

Operating Temperature . . . . .	0 to 70°C
Storage Temperature . . . . .	-65 to 125°C
Power Dissipation (Package)* . . . . .	750 mW

\*Device mounted with all leads welded or soldered to PC Board. Derated 6.3 mW/°C above 25°C.

## ELECTRICAL CHARACTERISTICS

All DC parameters are 100% tested at 25°C. Lots are sample tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC				MIN	TYP	MAX	UNITS	TEST CONDITIONS UNLESS NOTED OTHERWISE V+ = 12 V; V- = VDD = -12 V, VSS = 5 V, TA = 25°C	
1	SYSTEM (Notes 2 and 3)		Linearity	-1 -2	±1/4 ±1/2	1 2	Count	2 V Scale 200 mV Scale	
2			Noise (Note 1)		1/3 1/2	1 2	Count	2 V Scale 200 mV Scale	
3		NMRR			40		dB	fL = 50 or 60 Hz	
		PSRR			80				
4			Gain T.C.		5	15	ppm/°C		
5		Zero Drift		1	5	Count	TA = 25 to 75°C, CSTRG = 1 μF, RIN ≤ 100K Ω		
6	LD121A DIGITAL	POWER	VSS	4.5	5	5.5	V	Range Over Which Functionality is Guaranteed	
7			VDD	-10.8	-12	-13.2			
8			ISS	(Note 4)		14	25	mA	
9			IDD			-14	-25		
10		INPUTS	VINH	Comparator Input, Sign/OR/OR/ Blink (Note 5), Start, CLK IN	4.0			V	Guaranteed Input Threshold Voltages
11			VINL				0.5		
12			IINH	Sign/OR/UR (Note 5)		170	300	μA	VIN = 5 V
13			IINL	Start Convert, Clock		-150	-400		VIN = 0 V
14		OUTPUTS	VOH	Bit Lines, Sign/OR/UR Digit Strobes	2.4			V	I OH = -40 μA
15			VOL				0.6		I OL = 1.6 mA
16			VOH	M/Z	4.0				I OH = -150 μA
17			VOL				0.6		I OL = 0.8 mA
18			VOH	U/D	4.0				I OH = -0.5 mA
19			VOL				0.6		I OL = 0.8 mA
20	DYN	tp	Start Convert (Note 6)	20			μs		
21		fCLK		50		250	kHz	50% Duty Cycle	
22			Rep Rate (Strobes)		78		470	Hz	fCLK ÷ 640

## NOTES:

1. Bit width over which reading is stable 90% of the time.
2. System Parameters are not directly tested.
3.  $f_{CLK} = 163.84$  kHz,  $V_{REF} = 6.8$  V.
4. All outputs disconnected.
5. Pin characteristics only during  $D_4$  strobe time.
6. Minimum positive going pulse width to initiate a conversion.

## ELECTRICAL CHARACTERISTICS (Cont'd)

CHARACTERISTIC				MIN	TYP	MAX	UNITS	TEST CONDITIONS UNLESS NOTED OTHERWISE V+ = 12 V; V- = VDD = -12 V, VSS = 5 V, TA = 25°C	
23	L D 1 2 0 C J L I N E A R	P O W E R	V+		9	12	15	V	
24			V-		-9	-12	-15		
25			I+				3.5	mA	
26			I-				-3.5		
27		I N P U T	ISOURCE		-50	-100		μA	VIN = 2 V, Buff Out = 0 V
28			ISINK		400	800			VIN = -2 V, Buff Out = 0 V
29			IIN			2		pA	VIN = ±2.8V
30			IIN			40			TA = 70°C, VIN = ±2.8V
31		B U F F	CMRR			-72		dB	
32			VIN	(Note 7)	-5		5	V	
33		A Z	ISOURCE			-100		μA	
34			ISINK			800			
35			ISTRG			100		pA	TA = 70°C
36			VOFFSET		-50		50	mV	VOU T = 0 V
37				Switch Resistance (on) (Note 8)		6	20	kΩ	VSTRG = -4 V, IDS = 30 μA
38		R E F B U F	ISOURCE	Pin 8	-400	-800		μA	VIL (U/D IN), = 0.8 V, VO = 0 V
39			ISINK	Pin 8		100			VIH (U/D IN) = 2.0 V, VO = 2 V
40		I N T	ISOURCE	(Note 9)	-50	-100		μA	VIN (Int. IN) = -100 mV, VO = 0 V
41	ISINK		400		800			VIN (Int. IN) = 100 mV, VO = 0 V	
42			Output Swing	-10		8	V		
43	C O M P	VOU T		-5			V	RL = 10k to +5 V, AZ FILTER IN = 100 mV	
44		VOFFSET			±5		mV	I N T E G R A T O R O U T = 0 V	
45		IIH	M/Z, U/D Inputs			20	μA	VIH = 2.0 V	
46		IL				-100	μA	VIL = 0.8 V	

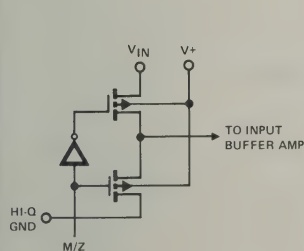
Typical values are for Design Aid Only, not guaranteed and not subject to production testing.

LD120-CMAM-A LD121A-IPDC VI

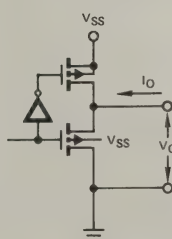
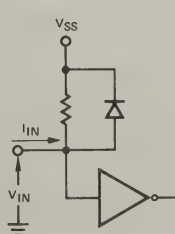
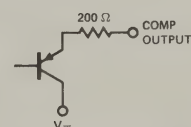
## NOTES:

1. Bit width over which reading is stable 95% of the time.
2. System Parameters are not directly tested.
3.  $f_{CLK} = 163.84\text{ kHz}$ ,  $V_{REF} = 6.8\text{ V}$ .
4. All outputs disconnected.
5. Pin characteristic only during  $D_4$  strobe time.
6. Minimum positive going pulse width to initiate a conversion.
7. Maximum voltage for  $V_{INPUT}$  (pin 1) or hi-quality GND (pin 2) for which linearity can be guaranteed. (Sum of normal and common mode input.)
8.  $V_{STRG}$  must be more positive than  $-4$  volts.
9. Reference Source Impedance must be less than  $10\text{ K } \Omega$ .

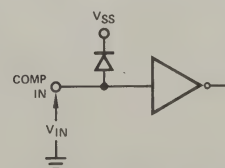
## INPUT/OUTPUT SCHEMATICS



LD120 Input

LD121A Output Buffers  
(Digits, Bits, Sign, M/Z U/D)LD121A Clock Input  
Start Convert

LD120 Comparator Output



LD121A Comparator Input



## FUNCTIONAL SYSTEM OPERATION

**Timing:** The external oscillator is divided to generate a 2- $\phi$  clock on the synchronous digital chip. A time base generator divides the clock frequency into sampling intervals of 49,152 pulses of which 16,384 pulses are the Auto-Zero interval and 32,768 pulses are the measure interval.

**Auto-Zero Interval:** The connection diagram in Figure 1 illustrates the system during the Auto-Zero interval. The input buffer is switched to reference ground and supplies a current equal to its offset voltage divided by  $R_2$  to the integrator summing mode. The U/D buffer is toggled by the digital processor between  $V_{REF}$  and ground with a 50% duty cycle. This results in a current flow equal to  $V_{REF}/R_1$  to the summing node half of the time. The AZ capacitor,  $C_{STRG}$ , assumes a voltage,  $V_{STRG}$ , that is equal to the average value of integrator output. The AZ buffer supplies a current to the summing node equal to the  $V_{STRG}$  voltage divided by  $R_3$ .

The system will reach an equilibrium when the sum of the DC currents into the summing node equal zero. At this time, the current through  $R_3$  equals  $-\frac{1}{2} V_{REF}/R_1$  plus the small currents necessary to cancel the offset of the

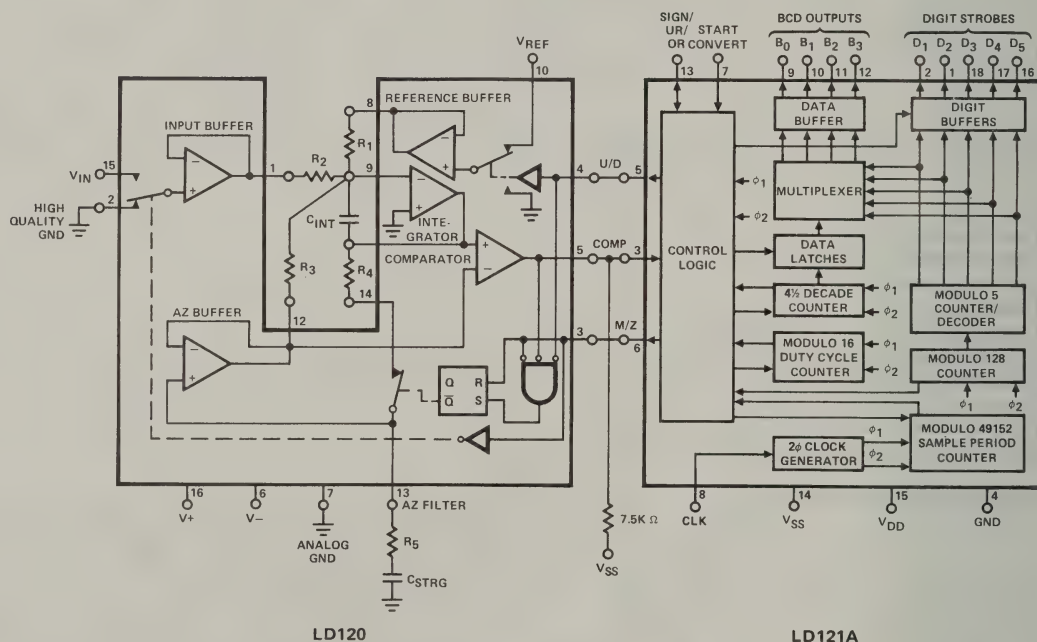
input buffer and integrator input bias current. Capacitor  $C_{STRG}$  "stores"  $V_{STRG}$  when the AZ switch opens at the end of the Auto-Zero interval. The digital BCD counter is inactive during Auto-Zero. It is reset to zero during the last clock pulse of the Auto-Zero interval.

## THE U/D CONTROL DURING THE MEASURE INTERVAL

The U/D buffer is switched to  $V_{REF}$  when the U/D control is low. In this state the currents through  $R_1$  and  $R_3$  sum to  $\frac{1}{2} V_{REF}/R_1$ . A high level on the U/D control connects the U/D buffer to ground. During this state the sum of the currents through  $R_1$  and  $R_3$  sum to  $-\frac{1}{2} V_{REF}/R_1$ . In one clock cycle, a charge equal to  $V_{REF}/2R_1f_{IN}$  coulombs is either added or subtracted to the integrator capacitor. The BCD counter is decremented for each addition of this quantized charge and incremented for each subtraction of quantized charge.

## THE MEASURE ALGORITHM

The input is connected to  $V_{IN}$  during the measure interval and supplies a current to the integrator equal to  $V_{IN}/R_2$ .



Connection Diagram  
Figure 1



## FUNCTIONAL SYSTEM OPERATION (Cont'd)

This causes the integrator output to move away from  $V_{STRG}$ . The digital processor attempts to keep the integrator output near  $V_{STRG}$  by adding or subtracting quantized charge to  $C_{INT}$ . The net amount of charge required to accomplish this is totaled by the BCD counter. The BCD count at the end of conversion equals the number of charge parcels necessary to cancel the input current supplied through  $R_2$ . The resulting count is proportional to the voltage at  $V_{IN}$ .

### U/D DUTY CYCLE CONTROL DURING THE MEASURE INTERVAL

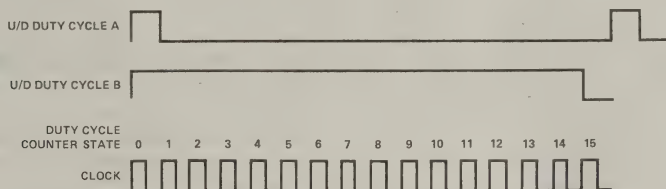
The digital processor contains a modulo 16 duty cycle counter that provides the U/D control output. This counter examines the state of the comparator once each 16 clock cycles during state 15. If the comparator is high, the U/D control will be high for one cycle and low for 15 cycles in the next 16 clock cycle period of the duty cycle counter. If the comparator output is low, the U/D control will be high for 15 cycles and low for one cycle in the next period of the duty cycle counter. Figure 2 illustrates these waveforms. The effect of these two duty cycles is to source or sink a net 14 charge parcels to  $C_{INT}$ , thus driving the

integrator output toward  $V_{STRG}$  and accumulating counts in the BCD counter in groups of 14 counts. This dual duty cycle control technique results in a fixed number of U/D control transitions, regardless of the value of  $V_{IN}$ ; therefore, these transitions cannot cause linearity error. The first few periods of the measure interval are illustrated in Figure 3 for a negative  $V_{IN}$ .

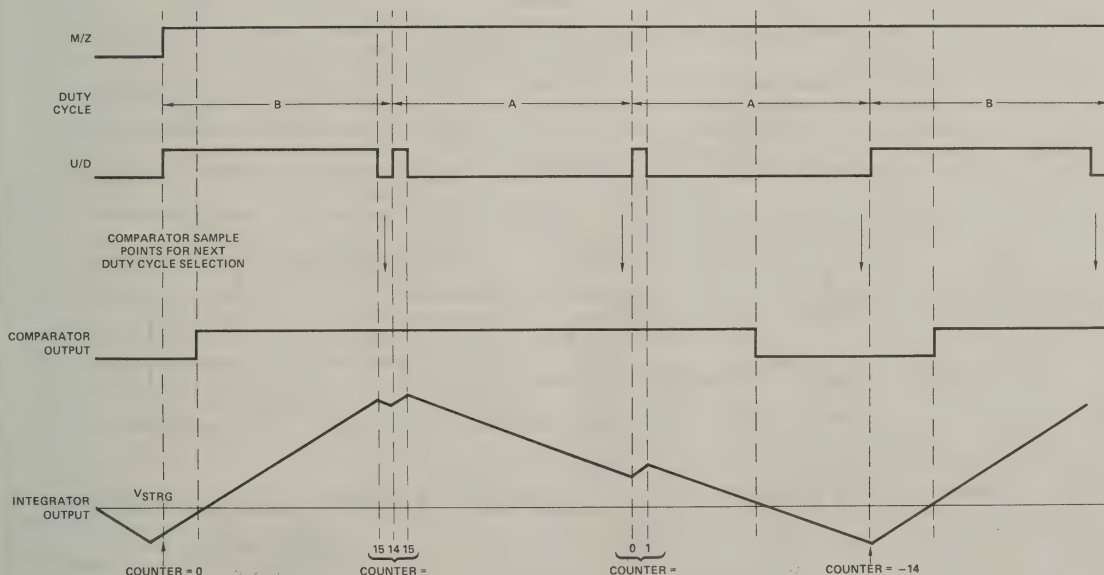
### AUTO-ZERO OVERRIDE AT THE END OF MEASURE

The BCD counter contents equal a multiple of 14 counts at the end of the measure interval. A residual voltage on  $C_{INT}$  represents the remaining unresolved portion of the input voltage. This voltage is cancelled and the corresponding counts accumulated during a brief override period at the start of the AZ interval. Normal AZ interval action is inhibited until this residual count is resolved.

The override period starts at the end of the Measure Interval. The input buffer is switched to reference ground as no additional charge is desired from  $V_{IN}$ . The U/D control is set high. After the comparator goes high, the U/D control is switched low at the next state 8 of the duty cycle counter. The next transition of the comparator ends the



Modulo 16 Dual Duty Cycle Counter Waveforms  
Figure 2



Measure Interval Timing ( $V_{IN} \approx -1 V$ )  
Figure 3

## FUNCTIONAL SYSTEM OPERATION (Cont'd)

conversion and the BCD counter is synchronously inhibited. The output latches are updated on the next clock pulse with the sign and contents of the BCD counter. The override period ends (end of conversion) and normal AZ action is initiated by the closing of the AZ switch. The duty cycle counter now drives the U/D control high during states 0 through 7 and low during states 8 through 15 for the required AZ interval 50% duty cycle.

Figure 4 illustrates the events at the end of the measure interval. The slope of the dotted lines is proportional to the unknown current through  $R_2$ .

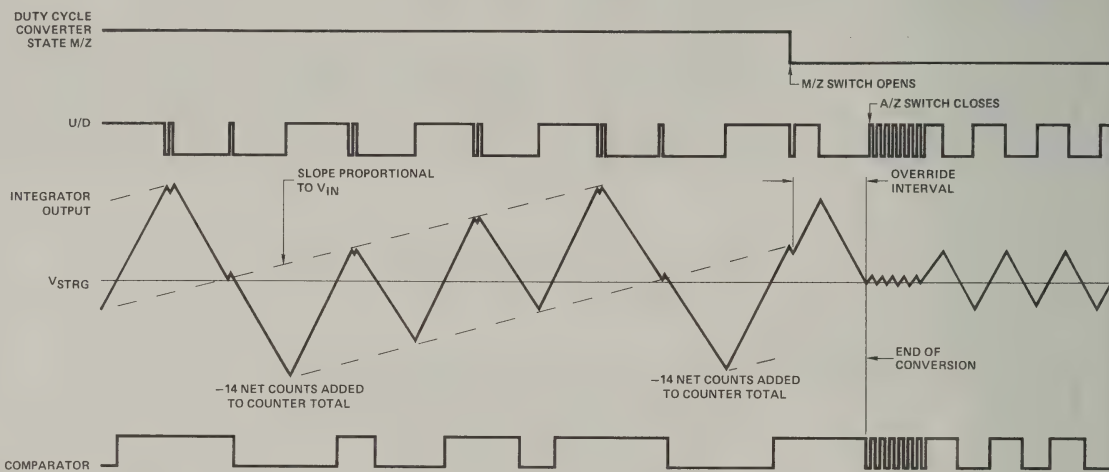
The self oscillation following the override period keeps  $V_{INT}$  near  $V_{STRG}$  until sync is achieved with the duty cycle counter. This feature eliminates large transients on

$C_{STRG}$  and results in highly stable Auto-Zero loop characteristics.

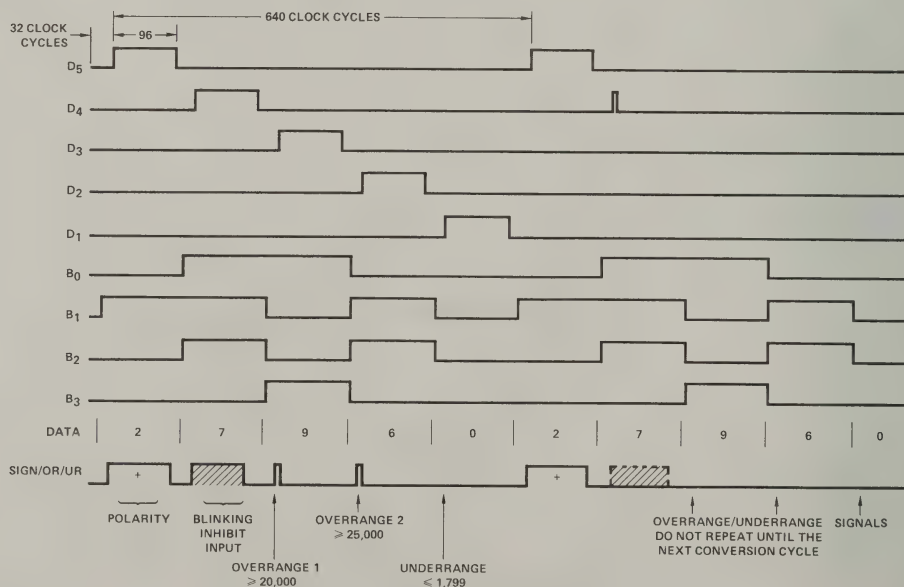
## DIGITAL INTERFACE FUNCTIONAL DESCRIPTION

**BCD Outputs— (Pins 9, 10, 11 and 12):** The output latch contents are time multiplexed in a digit serial, bit parallel fashion through 4 push-pull TTL compatible output buffers. A high level (sourcing current from  $V_{SS}$ ) indicates a one and a low level (sinking current to ground) indicates a zero.  $B_0$  is the least significant Bit. Figure 5 illustrates the timing relationship. All BCD outputs are valid during digit strobe time.

**Digit Strokes—(Pins 1, 2, 16, 17 and 18):** Figure 5 indicates the operation of these outputs. The strobes are TTL compatible. Only one strobe is high at one time. The strobe period



Algorithm Waveforms at the End of the Measure Period  
Figure 4



LD121 Digital Output Timing Diagram  
Figure 5

**FUNCTIONAL SYSTEM OPERATION (Cont'd)**

is equal to 640 clock cycles with a 15% duty cycle. An inter-digit blanking period of 32 clock cycles permits easy interface with gas discharge displays. The strobe sequence is  $D_5$  (MSD),  $D_4$ ,  $D_3$ ,  $D_2$ ,  $D_1$  (LSD).

**Clock Input (Pin 8):** Pin 8 requires an external clock input. The system operates from the positive clock transition allowing a 30 to 70% duty cycle in the external oscillator waveform. To maintain the linearity specifications of the A/D converter set the short term stability of this oscillator should be better than 1 part in  $2 \times 10^4$ .

**Sign/Ovrange/Underrange (Pin 13):** This pin operates as a TTL compatible output during  $D_1$ ,  $D_2$ ,  $D_3$  and  $D_5$  strobe times and as an input during  $D_4$  strobe time. Figure 5 indicates the timing relationship. Information is presented to this output as follows:

**At  $D_5$  Time** — Polarity is indicated by a high level for positive and a low level for negative. It is valid approximately 0.25  $\mu$ sec after  $D_5$  goes high until the end of each  $D_5$  strobe.

**At  $D_4$  Time** — The output buffer assumes a high impedance state. An input latch samples the voltage level imposed on this pin during  $D_4$  time. A high level will inhibit the overrange blinking (digit strobes are suppressed during zero interval). An internal pull down resistor will hold the pin voltage low if the pin is unconnected or the load is high impedance. An alternative method for selecting overrange blinking is the choice of output buffer. A TTL buffer connected to pin 13 provides a pullup inhibiting overrange blinking. A NPN buffer driver provides a pulldown yielding normal overrange blinking.

**At  $D_3$  Time** — If the count is equal to or greater than 20,000, a single positive going pulse will occur at the beginning of the first  $D_3$  time after the end of conversion cycle. The pulse width equals one clock cycle. The overrange blinking is momentarily inhibited when overrange pulses are present to prevent the display blinking feature from interfering with the decoding of the overrange output.

**At  $D_2$  Strobe— Time** A second overrange pulse occurs at the beginning of the first  $D_2$  time, after the end of conversion, if the count is equal or exceeds 25,000 counts.

**At  $D_1$  Strobe— Time** A single pulse occurs at the beginning of the first  $D_1$  time after the end of conversion, if the count is less than 1800 counts.

All overrange and underrange signals are one clock pulse wide. They occur only once per measure/zero cycle.

**Start Conversion (Pin 7):** A low level on this TTL compatible input holds the system in the zero mode continuously. A positive going pulse at least one clock time wide initiates one conversion cycle within 16 clock cycles after system has

completed minimum auto zero cycle. The digital data is valid after 32,850 clock cycles. A static high level on this input provides normal cyclical operation. An internal pull up resistor allows this input to remain unconnected when conversion control is not desired.

**APPLICATIONS**

1. The recommended supply voltages are:

$$\begin{array}{ll} V_{+} = 12 \text{ V} \pm 10\% & V_{SS} = 5 \text{ V} \pm 10\% \\ V_{DD}, V_{-} = -12 \text{ V} \pm 10\% & V_{REF} = 2 \text{ V to } 10 \text{ V} \end{array}$$

2. The reading is essentially the proportionality of  $V_{IN}$  compared to  $V_{REF}$  as shown in the gain equation:

$$\text{READOUT} = (V_{IN} - V_{HI-Q \text{ GND}}) \cdot \frac{R_1}{R_2} \cdot \frac{65,536}{V_{REF}}$$

$R_1$  is independent of the U/D switch resistance due to the incorporation of the U/D buffer amplifier in the LD120. Gain can be calibrated either by varying  $V_{REF}$  or trimming the resistance of  $R_1$  to obtain the correct full scale reading.

3. The output of the integrator should always be more positive than  $-9 \text{ V}$  (for  $V_{DD} = -12 \text{ V}$ ) to obtain specified accuracy:

$$V_O (\text{min}) > -9 \text{ V}$$

$$V_O (\text{min}) = -\frac{V_{REF} R_3}{2R_1} - \frac{15}{f_{CLK} C_{INT}} \left[ \frac{V_{REF}}{2R_1} + \frac{V_{IN} (\text{max})}{R_2} \right]$$

Change value of  $C_{INT}$  to set  $V_{INT}(P-P)$ .

Large integrator swing provides the best performance.  $V_{INT}(P-P) = 6$  to 8 volts is recommended.

$$V_{INT}(P-P) = \frac{30}{f_{CLK} C_{INT}} \left[ \frac{V_{REF}}{2R_1} + \frac{V_{IN} (\text{max})}{R_2} \right]$$

4. Although any oscillator frequency from 50 kHz to 250 kHz can be used, frequencies that provide integer number of line frequency cycles per measure period provide maximum line noise rejection. These frequencies are:

$$f_{CLK} = \frac{32,768 F_{LINE}}{n}, \quad n = 8, 9, 10, \dots 40$$

$f_{CLK} = 163,840$  is popular since it provides both 50 and 60 Hz rejection.

5. The sampling rate =  $f_{CLK}/49,152$  cycles/sample.
6. After a start conversion pulse, data is valid 32,850 clock pulses later and remains valid until at least 32,768 clock pulses after the next start pulse. During continuous cycle operation, data is assured valid when M/Z is high or 100 clock cycles after the one/zero transition of M/Z.
7. Any capacitive coupling between U/D and Comp. is detrimental to proper algorithm operation. PC board layouts should not allow these traces to be adjacent.



## APPLICATIONS (Cont'd)

8. All power supplies should be capacitively bypassed to ground for maximum count stability.
9.  $C_{INT}$  and  $C_{STRG}$  should be selected for low leakage. Silvered mica is recommended for  $C_{INT}$  and mylar for  $C_{STRG}$ . Polypropylene capacitors also work well for both  $C_{STRG}$  and  $C_{INT}$ .

10. For a given leakage into  $C_{STRG}$  of  $I_{STRG}$ :

$$\Delta V_{STRG} = \frac{\Delta t I_{AZ}}{C_{STRG}}$$

$$\text{where } \Delta t = \text{a measure interval} = \frac{2}{3} \frac{1}{F_{SAMPLE}}$$

$\Delta V_{STRG}$  will inject a  $\Delta I$  integrator of  $\Delta V_{STRG}/R_3$

Now a  $\Delta I$  integrator would have been equivalent to a  $\Delta V_{IN}/R_2$

So the equivalent input drift is

$$\Delta V_{IN} = \frac{1}{2} \frac{R_2}{R_3} \frac{2}{3} \frac{I_{STRG}}{F_{SAMPLE} \cdot C_{STRG}}$$

the  $\frac{1}{2}$  factor is provided by integrator action.

Example: We wish to see 1 count (0.1 mV of  $\Delta V_{IN}$  on the 2 V range) of drift for the circuit of Figure 7 with  $I_{STRG} = 100 \text{ pA}$  @  $70^\circ \text{C}$ . What  $C_{STRG}$  is needed?

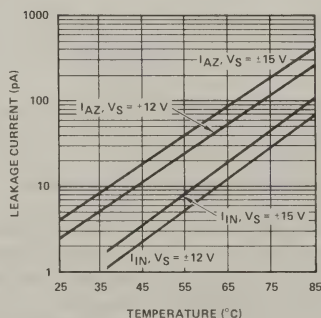
Answer:

$$C_{STRG} = \frac{R_2}{R_3} \frac{1}{3} \frac{I_{STRG}}{F_{SAMPLE} \cdot \Delta V_{IN}} =$$

$$\frac{100\text{K } \Omega}{62\text{K } \Omega} \times \frac{1}{3} \times \frac{10^{-10} \text{ F}}{3 \text{ Hz} \times 10^{-4} \text{ V}}$$

$$= 0.18 \mu\text{F Minimum}$$

Typical Leakage Over Temperature



11. Interfacing the LD120/LD121A to Microprocessors: A description of interfacing the LD120/LD121A to the 8080  $\mu\text{P}$  is given in AN77-3. Some of the timing details warrant description here.

The end-of-conversion is determined by gating  $\overline{M/Z} \cdot \overline{U/D} \cdot \text{COMP}$ . At this time, all BCD latches are updated with the contents of the latest conversion.

We recommend using the positive edge of  $\overline{M/Z}$  to interrupt the processor. Next, test for a high  $D_5$  digit strobe (MSD). Once  $D_5$  is high load the BCD data from  $B_0$ – $B_3$  lines and the polarity information from the  $\text{SIGN/OR/UR}$  line. Next delay 128 LD121A clock times (this assures that the  $D_4$  data is valid) then load  $B_0$ – $B_3$  lines containing the  $D_4$  data. Next delay another 128 LD121A clock times (this assures that the  $D_3$  data is valid) then load  $B_0$ – $B_3$  lines containing the  $D_3$  data. Repeat this process for  $D_2$  and finally the  $D_1$  (LSD) data load. In flowchart form (see Figure 6).

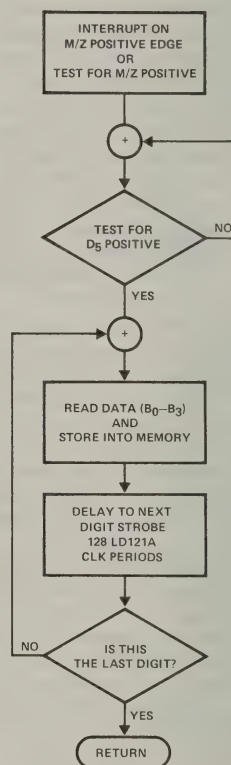


Figure 6



**CIRCUIT BENEFITS**

- Overrange Blinking
- $0 \rightarrow \pm 1.9999$  Input Voltages
- Zero Adjust to Null Offset Introduced by PC Board Leakages and Comparator

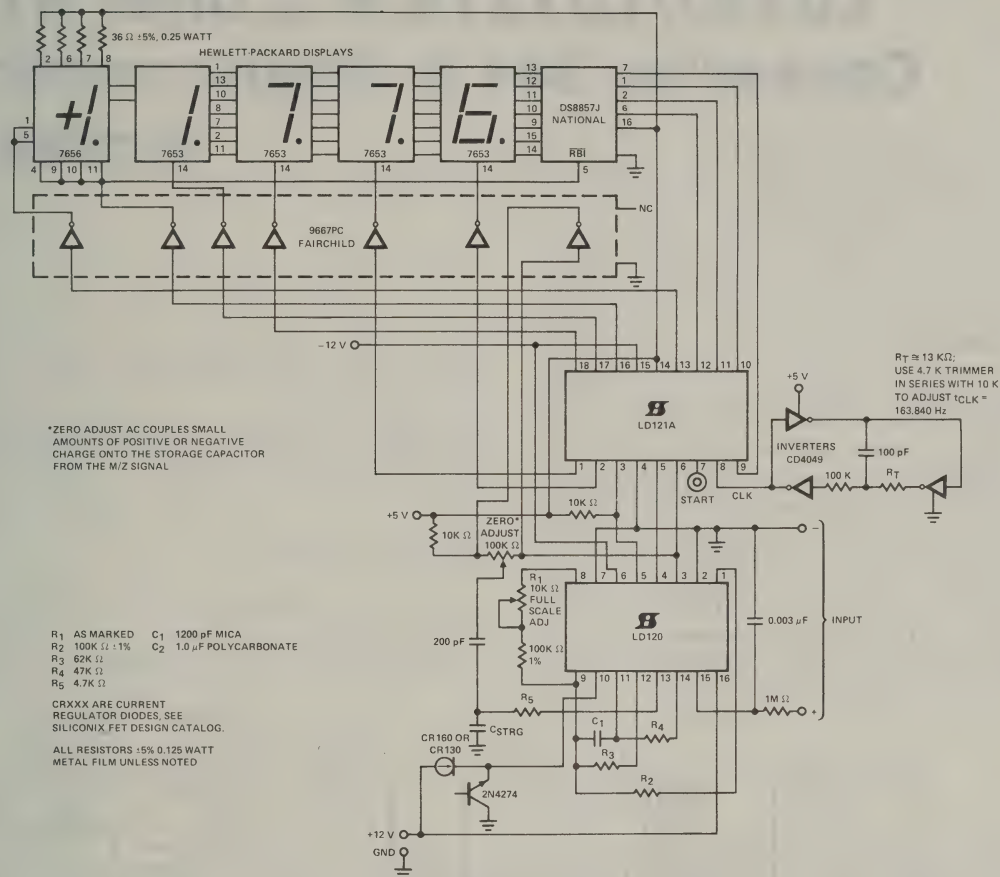


Figure 7

# Function/Application of the LD120/LD121A 4½ Digit A/D Converter Set in Measurement Systems

## INTRODUCTION

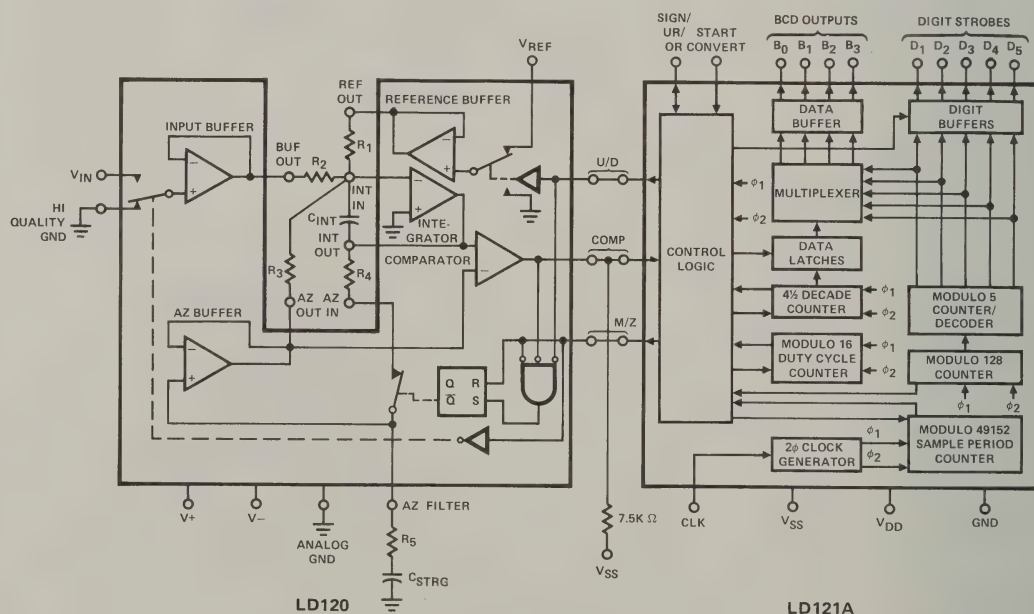
The Siliconix LD120 and LD121A Integrated Circuits permit the building of low cost and physically small 4-1/2 digit panel meters, voltmeters, and other A/D conversion systems where resolution and accuracy are of prime importance. The set can provide basic ranges of  $\pm 2$  V and  $\pm 200$  mV full-scale and, with an external amplifier and analog switch, can read  $\pm 20$  mV full-scale. The quantized feedback algorithm of A/D conversion provides inherent auto-polarity and auto-zero operation, and the PMOS/Bipolar technology of the LD120 analog chip provides  $>10^9 \Omega$  input impedance and buffered reference input. The set is flex-

ible with regard to analog signal range, external voltage reference level, and output display format.

This application note will describe the basic operation and circuit constants, and will develop some typical applications circuits.

## Description of Operation

There are two main periods in a sample of analog data; the auto zero period and the measure period. Descriptions of these periods will be referred to Figure 1.



Connection Diagram  
Figure 1

### Auto-Zero Interval

In the auto-zero period, the input buffer is connected to high-quality ground and the auto-zero buffer is connected to the integrator output. Ignoring up/down and transient waveforms for the moment, the DC currents presented to the integrator are:

$$I_{INT} = I_{BIAS, INT} = \frac{V_{OFFSET, INPUT BUFFER}}{R_2} + \frac{V_{OFFSET, AZ BUFFER}}{R_3} + \frac{V_{OFFSET, REFERENCE BUFFER}}{R_1} + \frac{V_{AZ, OFFSET}}{R_3} + \frac{V_{HI-Q}}{R_2}$$

$V_{AZ, OFFSET}$  is the fraction of the auto-zero voltage across CAZ which will null all the other quantities mentioned above. Also being injected into the integrator input is  $V_{REF}/2R_1$  since the up/down line is being toggled at 50% duty cycle by the LD121A. When the dynamics of the system settle out toward the end of the zero period, CAZ will have the voltage

$$V_{AZ} = V_{AZ, OFFSET} - \frac{R_3}{2R_1} V_{REF}$$

$-V_{REF} R_3/2R_1$  provides a reference quantity of exactly negative one-half the integrator input current injected by the reference current through  $R_1$ .

The auto-zero period is 16,384 clock times long.

### Measure Interval

During the measure interval, the input buffer is connected to  $V_{IN}$  and the auto-zero capacitor is disconnected from the integrator output. The quantity  $V_{AZ, OFFSET}$  remains on CAZ, and analog offsets are nulled out. Due to the quantity  $-V_{REF} R_3/2R_1$  being held on CAZ, an effective  $V_{REF}/2$  or  $-V_{REF}/2$  is applied through  $R_1$  when U/D is 0 and 1, respectively.

Referring to Figure 2, the U/D waveforms are of 2 kinds: 1 clock time up and 15 down; and 15 clock times up and 1 down. The LD121A logic generates these waveforms in response to the LD120 comparator output. The system attempts to return the integrator output to  $V_{AZ}$  regardless of the input. Since the integrator sees both input and reference currents simultaneously, its output does not vary far from  $V_{AZ}$ .

The BCD counter counts up once per clock time when U/D=1 and down once per clock time when U/D=0, causing the displayed count to be proportional to the amount of  $V_{REF}/2R_1$  that was required to null  $V_{IN}/R_2$  during the

measure interval. The charge balancing in the measure interval calculates so:

$$Q = \frac{V_{IN} - V_{HI-Q}}{R_2} \Delta t \equiv \text{Count} \frac{1}{f_{OSC}} \frac{V_{REF}}{2R_1}$$

where  $\Delta t = 32,768/f_{OSC}$  and is the measure period.

Rearranging,

$$\text{Count} = \frac{V_{IN} - V_{HI-Q}}{V_{REF}} \frac{R_1}{R_2} \cdot 65,536.$$

The measure interval cannot resolve single counts; it can only resolve multiples of 14 counts. Immediately after the measure and into the auto-zero period is the override period. The input buffer is reconnected to  $V_{HI-Q}$  and the CAZ switch is left open. The LD121A sends the integrator positive with respect to  $V_{AZ}$  (see Figure 3), then returns it to  $V_{AZ}$  potential, stopping when the LD120 comparator changes states, keeping track of the count in single clock times. The override period can exist a maximum of 56 clock times into the zero period, assuming a non-overload  $V_{IN}$ .

Since only 14 of the 16 counts in the U/D waveform produce net counts, there are  $\pm 28,672$  counts maximum out of the 32,768 clock times available.

### Component Selection

$R_1$  and  $R_2$ : The nominal currents into the integrator are 20  $\mu A$  full-scale through  $R_2$  and 80  $\mu A$  through  $R_1$ . These values are chosen for minimum system noise consistent with maximum amplifier linearities. Then

$$R_2 = \frac{V_{IN} (F.S.)}{20 \mu A}, \quad R_1 = \frac{V_{REF}}{80 \mu A}$$

$V_{REF}$  should be in the range of 2 V to 8 V, for reasons of system gain stability and noise characteristics. Some trimming of either  $R_2$  or  $R_1$  is required for exact full-scale reading.

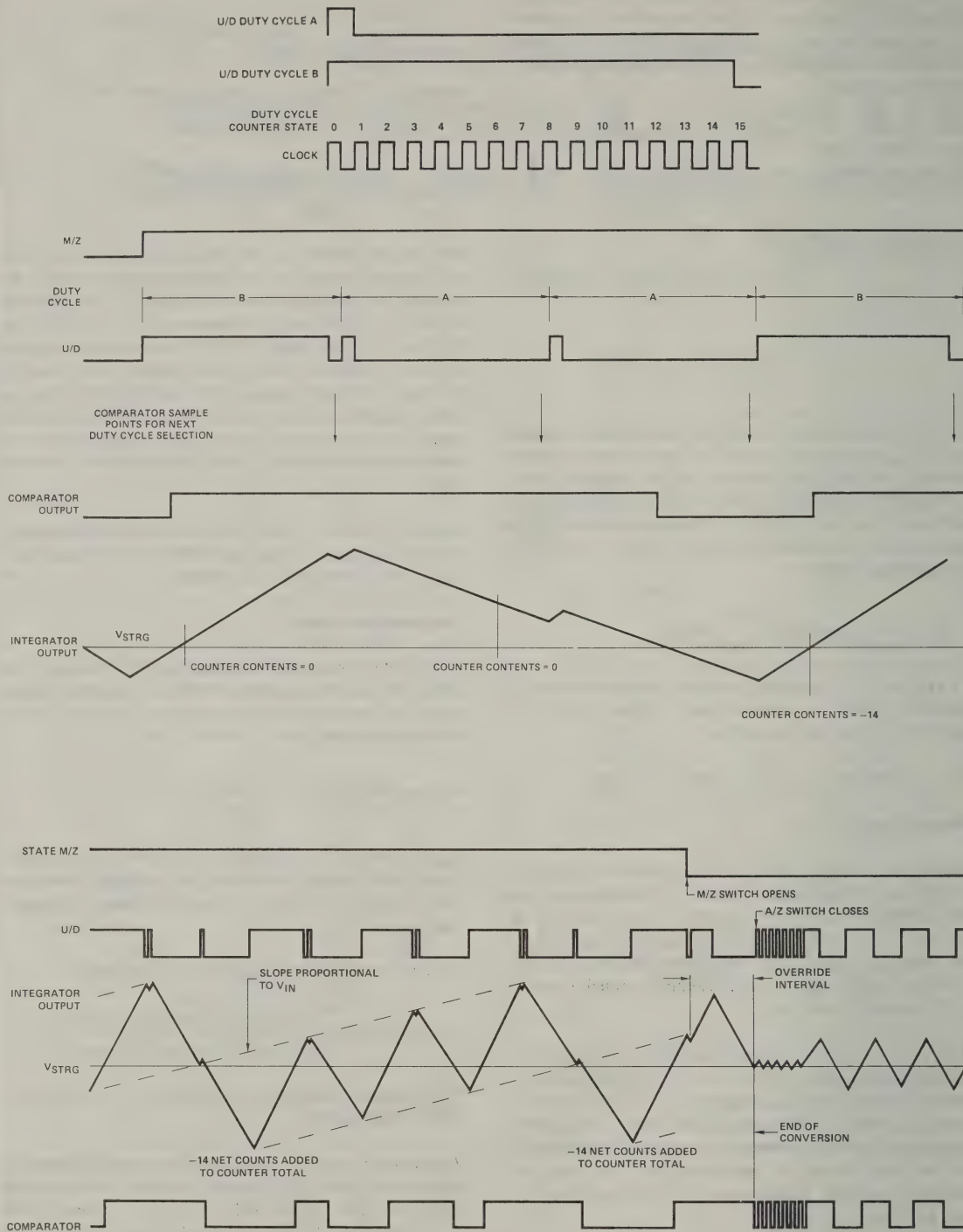
$R_2$  is determined by the equation previously given

$$R_2 = 65,536 R_1 \left[ \frac{V_{IN} (\text{FULL-SCALE}) - V_{HI-Q}}{V_{REF} \text{ Count (FULL-SCALE)}} \right]$$

The oscillator frequency is determined from  $f_{OSC} = 49,152 \times \text{Sample Rate}$ .

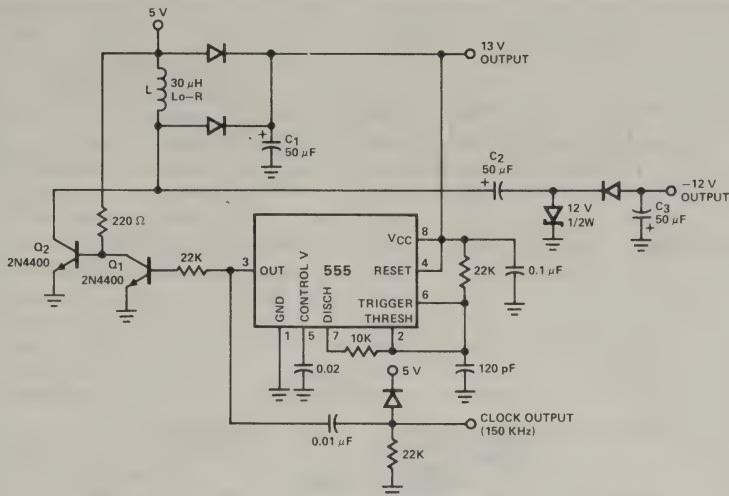
Values of  $R_3$  and  $C_{INT}$  are derived from the consideration that the integrator output should be at least 3 V from either supply rail. The negative rail is the one of interest, since  $V_{AZ}$  is negative. A starting point is to set the integrator AC swing at about 6 V p-p. Then

$$C_{INT} = \frac{V_{REF}}{R_1} \cdot \frac{1}{6 V} \cdot \frac{30}{f_{OSC}}$$



Up/Down and Integrator Waveforms  
Figure 2





**LD120/121A Power Supply and Clock**  
**Figure 3**

The factor of 30 results from the fact that 2 cycles, 1 up and 1 down, each having an effective 15 clock times before folding back for 1 clock time, are required to cause the 6 V p-p swing. The envelope of integrator waveform can be almost completely above  $V_{AZ}$  or below it; so a  $V_{AZ} = -3$  V is appropriate. Neglecting the offset components of  $V_{AZ}$ , which are relatively small, we have

$$-V_{AZ} \simeq V_{REF} \frac{R_3}{2R_1} + V_{HI-Q} \frac{R_3}{R_2},$$

and setting  $V_{AZ} \equiv -3$  V,

$$R_3 \equiv \frac{6R_1 R_2}{R_2 V_{REF} + 2R_1 V_{HI-O}} \Omega.$$

$C_{AZ}$  is chosen from the range of 0.1 to 1  $\mu\text{F}$ , as determined by zero drift considerations given in appendix A.

R<sub>4</sub> and R<sub>5</sub> are selected in consideration of settling time of the system in the auto-zero period. Typical values are 47K and 4.7K for C<sub>INT</sub> = 1200 pF at 3 samples/second.

As for component quality, R<sub>3</sub>, R<sub>4</sub>, and R<sub>5</sub> are non-critical. R<sub>1</sub> and R<sub>2</sub> should be metal film or wirewound. C<sub>INT</sub> should be mylar or better quality and C<sub>AZ</sub> must be mylar, polycarbonate, or polypropylene, the latter being best with regards to dielectric absorption characteristic.

Finally, the oscillator must be short term stable, even though long term drift is not a problem.

## APPLICATIONS CIRCUITS

## Power Supplies

The plus and minus 12 V supplies can be obtained from a standard 5 V supply, as well as the required oscillator signal, with the circuit in Figure 3.

The 13 V output is pulled to 4.3 V upon connecting 5 V input. This allows the 555 to start oscillating, driving Q1 and Q2. Q2 pulls current through L for approximately 50% of the time, and releases it to allow the flyback voltage to charge C1. The negative edge of Q2's collector waveform charges C3 through its associated rectifier circuitry, and the 12 V zener absorbs all unused energy available from L in shunt regulator style.

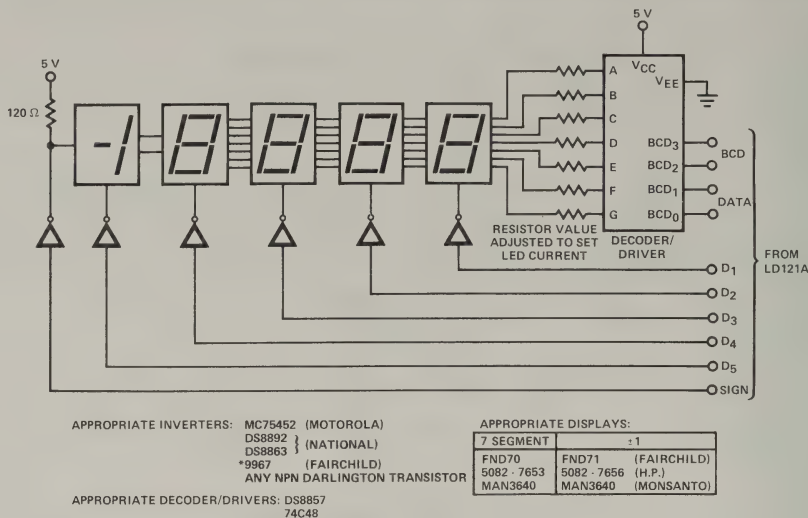
The circuit performs adequately for a supply of 4.5 V to 5.5 V input, and the 555 being run from the 13 V output, is not modulated by the 5 V power line noise.

## Display Formats

Figures 4 and 5 show common cathode and anode type light-emitting diode (LED) display circuits. Both are multiplexed to conserve supply current.

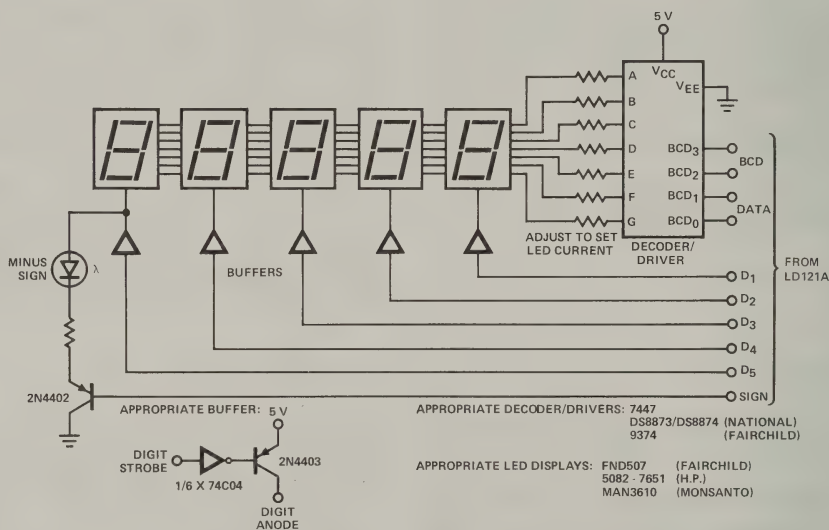
The duty cycle of each strobe is 15%. If an average LED current of 5 mA is desired, each digit strobe switch must be able to pass  $5 \text{ mA} \times 7 \text{ segments} / 0.15 = 233 \text{ mA}$ , necessitating the use of strong drivers. Also the decoder/driver must be able to pass  $5 / 0.15$  or 33 mA. The use of high-efficiency LED's, running at an average of 3 mA, would be advisable, but not necessary.

Figure 5 shows a simple circuit for leading zero blanking when a decoder/driver has that function built in. There are 2 flip flops in the circuit. D5 initiates the G3/G4 latch to begin a scan in the order D5-D4-D3-D2-D1. G3 enables the G1/G2 latch until DX resets G4 and G3, disabling G1/G2. G1 and G2 form a ones-catching latch through RBI and RBO; RBO = 1 resets the latch, disabling RBI. Thus either DX or RBO can terminate a zero blanking sequence.



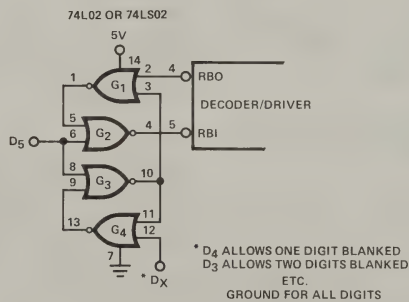
Common Cathode LED Display ( $\pm 19,999$  Counts max. with Blinking)

Figure 4



Common Anode LED Display ( $\pm 28,672$  Counts max. without Blinking)

Figure 5a



Leading Zero Blanking

Figure 5b

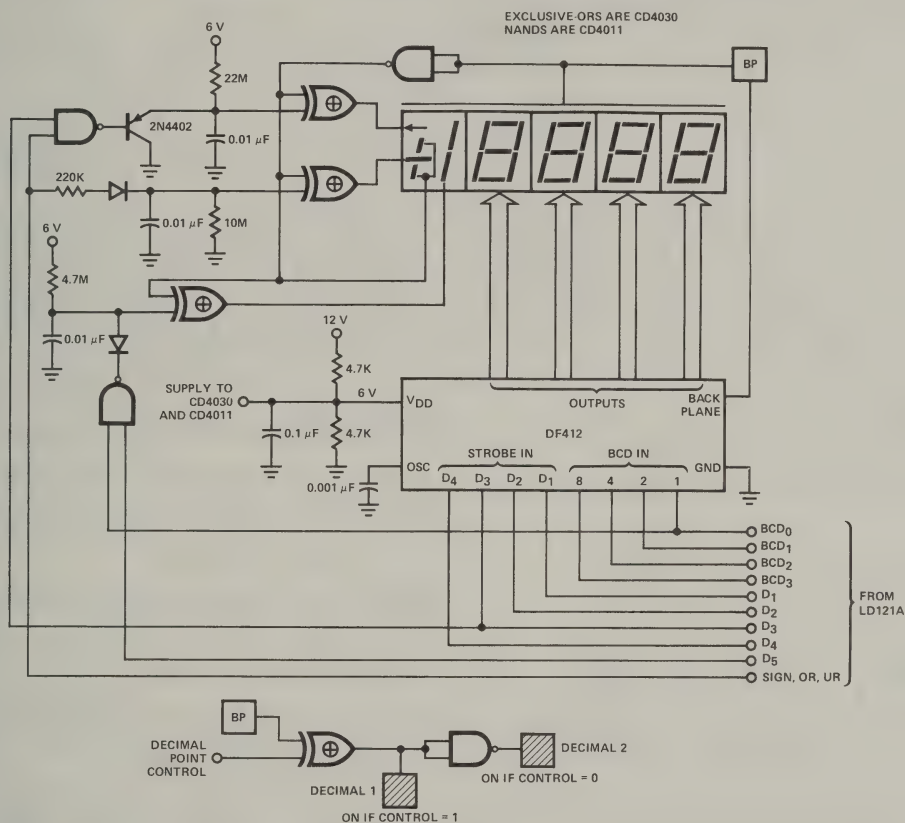
Figure 6 shows an LCD display circuit. The Siliconix DF412 accepts BCD data in strobe fashion, latches it, and presents decoded 7-segment drive to the LCD display. The overrange, sign, and leading "1" are provided by CMOS decoding and RC memory circuits through the exclusive-or LCD drivers. The effective LCD drive is 12 V p-p with a 6 V supply for the DF412 and CD4030.

### Preamplifiers

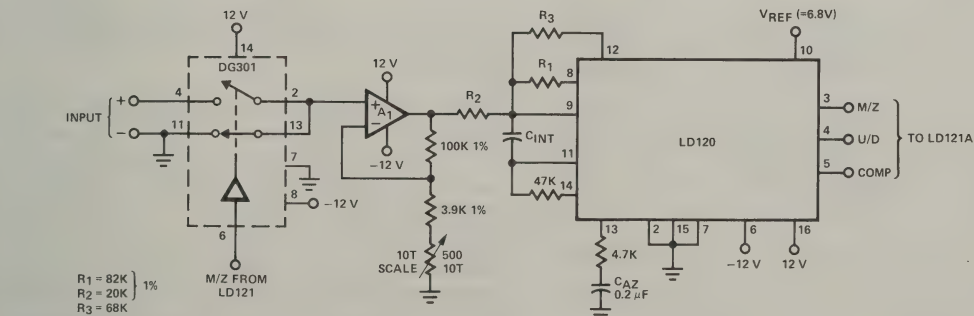
A feature of the quantized-feedback conversion is the ability to use external preamplifiers within the auto-zero loop. This allows a preamp that is quiet but has poor DC

characteristics to be used down to a stable  $1 \mu\text{V}/\text{LSB}$  sensitivity. This is necessary for sensitivities greater than 200 mV full-scale because the PMOS transistors of the LD120 do not have good  $1/F$  noise characteristics.

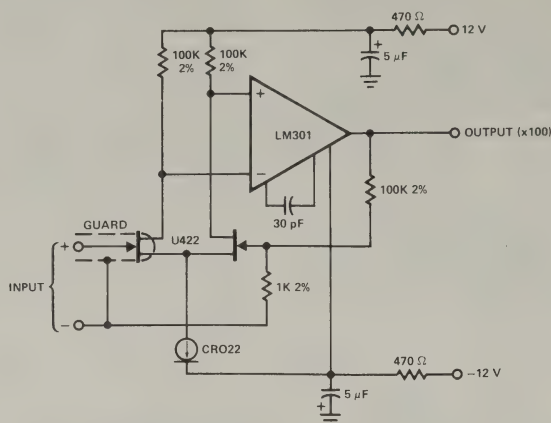
Figure 7 shows the arrangement for a 20 mV full-scale front end. If an extremely low source impedance were used, such as thermocouple, then an amplifier such as the LM201A could be used for  $A_1$ . For higher impedances, lower bias currents are required until at about  $1\text{K} \Omega$  or above, a JFET amplifier will be required. Note that MOS input op-amps are not quiet enough.



LCD Display  
Figure 6



20 mV F.S. Meter (Front End)  
Figure 7

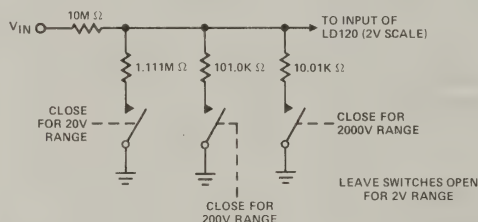


Ultra-Low-Leakage Preamp  
Figure 8

Even the BI-FET op-amps are only good for a 20K  $\Omega$  input resistance up to 75°C. The circuit of Figure 8 has an input leakage of only 2 pA typical at 75°C and would be usable with 1M  $\Omega$  input resistance. Although not covered here, there are ways to reduce leakage effects over temperature by a factor approaching 10.

### Auto-Ranging Voltmeter

The usual auto-ranging voltmeter simply has an input attenuator whose division ratio is controlled by analog switches:



The problem with this approach is that only 10 pA of total leakage at the divider node causes 1 count of offset on the 2 V range. 10 pA is not easily met over temperature.

The circuit of Figure 9 is another approach to the problem. The input signal is fed through a 10M  $\Omega$  input resistor to the summing junction of an inverting-gain op-amp whose gain is controlled in 2 ranges. The output of the op-amp is fed through 2  $R_2$  resistor paths to the integrator input of the LD120; the input buffer amplifier and switch of the LD120 are not used. Here is a table of the resistance paths used in each scale excluding the trimmers:

Range	Op-Amp Feedback	$R_2$ to integrator
2 V	3.9M $\Omega$	390K $\Omega$    43K $\Omega$
20 V	3.9M $\Omega$	390K $\Omega$
200 V	3.9M $\Omega$    39K $\Omega$	390K $\Omega$    43K $\Omega$
2000 V	3.9M $\Omega$    39K $\Omega$	390K $\Omega$

The U426 JFET monolithic pair has extremely low leakage and is used as the input measure/zero switch. During the zero period Q1 is on and Q2 is off so that the op-amp sees 10M  $\Omega$  +  $R_{DS}$  FET 1 to ground as an input. During the measure interval, Q1 is OFF and Q2 is ON so that the op-amp sees 10M  $\Omega$  +  $R_{DS}$  FET 2 in series with the input voltage. Since the input (and feedback) resistances are identical in measure and in zero the auto-zero voltage of the LD120 suppresses input offsets over temperature.

Digital control of the range switches is accomplished by decoding the LD121A overrange and underrange outputs and driving a 2-bit counter with the resulting "count up" and "reset downward" signals.

Although not tried here, a 200 mV range seems possible, but does require 5 scale ranges.

Calibration is done in this order:

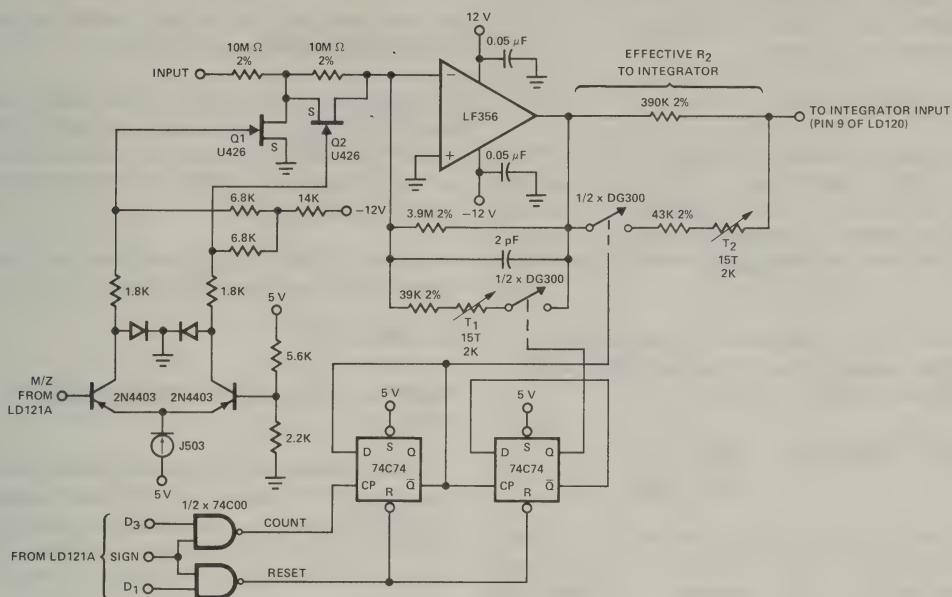
- (1) Offset zero is set with input shorted.
- (2) The LD120 scale factor is adjusted with the auto ranger in the 20 V range.
- (3) Trimmer 2 is adjusted for scale factor in the 2 V range.
- (4) Trimmer 1 is adjusted on the 200 V range.

### Microprocessor Interface

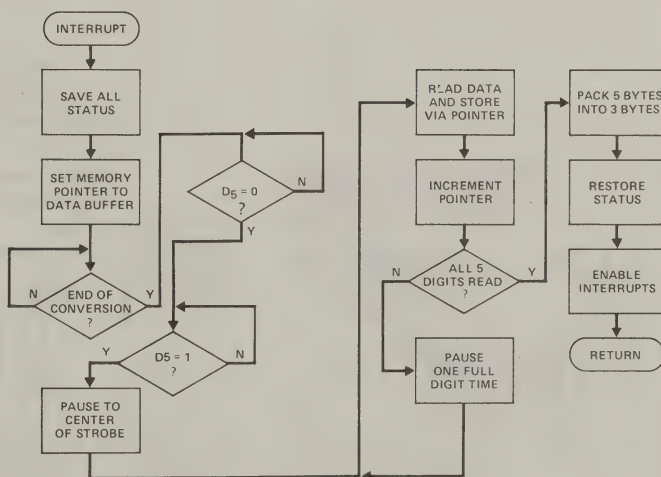
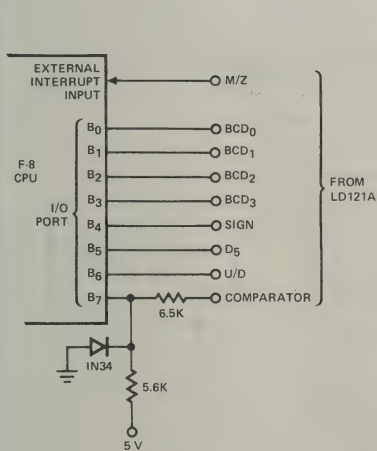
This circuit is used with the F8 series microprocessor, but the general approach taken is applicable to many processors.

Figure 10 shows the port wiring and flowchart. The falling edge of the M/Z line is used to request an interrupt from the processor, whereupon the I/O program waits for a decoded end of conversion. This end of conversion signal occurs when U/D = 0, M/Z = 0, and comp. = 0. The program then waits for D5 to occur to synchronize subsequent data pickup. A delay causes the actual BCD data to be read in the middle of the strobe, and all subsequent strobes are sampled in the middle of their intervals. After 5 strobes have been read in, the data is packed and left in a location of memory.





Auto-Ranging Amplifier; 2-2000 V Ranges  
Figure 9



F-8/LD121A Interface  
Figure 10

## APPENDIX A: ERROR TERMS

**Zero Drift** — The main source of zero drift is leakage from the input and auto zero buffers. Figure 11 shows typical input and auto zero leakages over temperature. The error component due to  $I_{IN}$  is simply

$$\Delta V_{IN} = \Delta I_{IN} \cdot R_{SOURCE}$$

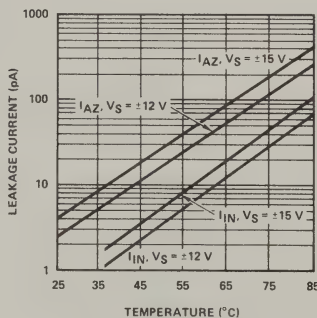
For a  $1M\ \Omega$  input resistance, and  $\Delta I_{IN} = 30\text{ pA}$  at  $75^\circ\text{C}$ ,  $\Delta V_{IN} = 30\ \mu\text{V}$ , corresponding to a 0.3 bit offset at 2 V full-scale, and 3 count offset at 200 mV full-scale. This offset can be reduced by reducing  $R_{SOURCE}$  or by inserting a compensating  $R_{SOURCE}$  between  $V_{HI-Q}$  and ground.

The drift due to  $I_{AZ}$  is independent of scale factor, and is caused by the voltage on  $C_{AZ}$  drifting during the measure interval. The magnitude of drift will be

$$\Delta V_{AZ} = \frac{I_{AZ} \cdot T_{MEASURE}}{C_{AZ}} = \frac{I_{AZ} \cdot 32,768}{C_{AZ} \cdot f_{OSC}}$$

This will cause an effective input current to the integrator of  $\Delta V_{AZ}/2R_3$ , the factor two resulting from the fact that the ramp of auto-zero drift is averaged by the algorithm. This input current due to drift is analogous to an input signal of  $\Delta V_{AZ} R_2/2R_3$ , so the count drift is

$$\Delta \text{Count} = \frac{\Delta I_{AZ}}{C_{AZ} f_{OSC} V_{REF}} \cdot \frac{R_1}{2R_3} \cdot 2.15 \times 10^9$$



Typical Leakage Over Temperature  
Figure 11

So given  $\Delta I_{AZ} = 100\text{ pA}$  when up at  $70^\circ\text{C}$ ,  $R_1 = 60K = R_3$ ,  $C_{AZ} = 0.1\ \mu\text{F}$ ,  $f_{OSC} = 150\text{KHz}$ , and  $V_{REF} = 6.2\text{ V}$ ,  $\Delta \text{Count} = 1.16$  due to  $\Delta I_{AZ}$  only.

The drift caused by thermocouple junctions on the LD120 is much less than that caused by leakages.

**Gain Drift** — Full-scale gain drift is caused mainly by changes in  $V_{REF}$ . One count in 20,000 stability per degree C is  $50\text{ ppm}/^\circ\text{C}$ , so the zener reference should have at least  $10\text{ ppm}/^\circ\text{C}$  stability and the system burned-in to reduce long term drift.

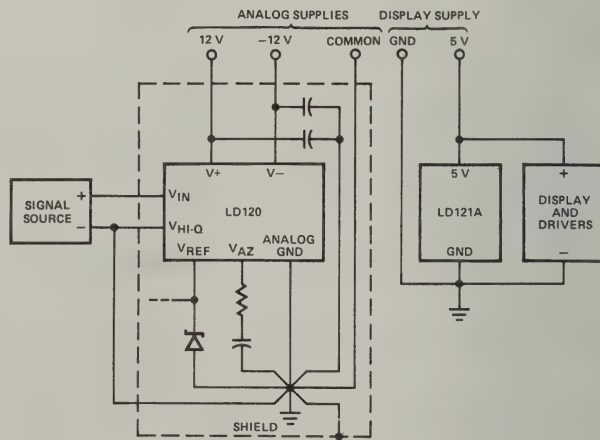
The resistors at  $R_2$  and  $R_1$  should track each other over temperature at least as well as the tempo of the reference.

## APPENDIX B

**Grounding** — The optimum grounding scheme is shown in Figure 12.

The main considerations are: analog ground is common to  $V_{REF}$ ,  $C_{AZ}$ ,  $\pm 12\text{ V}$  commons,  $\pm 12\text{ V}$  bypass, ground of the signal source, common power ground, case ground; isolation of currents in the 5 V circuits from those of analog grounds; a 3-wire input connection for remote signal sources.

These connection methods will alleviate AC and DC pickup in signal inputs and integrator positive input (analog ground) from noise currents caused by the display and AC environment.



LD120/LD121A Grounding System  
Figure 12

Problem	Causes
Jittery Display	<ul style="list-style-type: none"><li>fOSC is not stable (short-term)</li><li>AC voltage on VIN, VHI-Q, power supplies, or VREF</li><li>AC fields passing through unshielded circuit board</li><li>R1, R2, or R3 being carbon composition type</li><li>Excessively small full-scale sensitivity implemented</li><li>VAZ or VREF too small</li></ul>
Offset Drift	<ul style="list-style-type: none"><li>Excessive input resistance or CAZ too small (see appendix A)</li><li>Circuit board leakages excessive due to flux or moisture absorption</li><li>A variable offset in grounding system</li><li>Poor quality capacitors for CINT or CAZ</li><li>Sample rate too slow (&lt;1 sec)</li><li>Thermocouple junctions in the 200 mV range</li></ul>
Poor Linearity	<ul style="list-style-type: none"><li>Poor quality CINT</li><li>V+ or V– less than 10 V</li><li>Circuit board leakages to CINT</li><li>Noise pickup on U/D or loading of U/D</li><li>VREF modulated by display ground currents</li></ul>
No digit strobes from LD121A	<ul style="list-style-type: none"><li>Clock not functioning</li><li>Some terminal of the LD121A more positive than VSS</li></ul>

# Design Aid of the LD120/LD121A 4½ Digit DVM

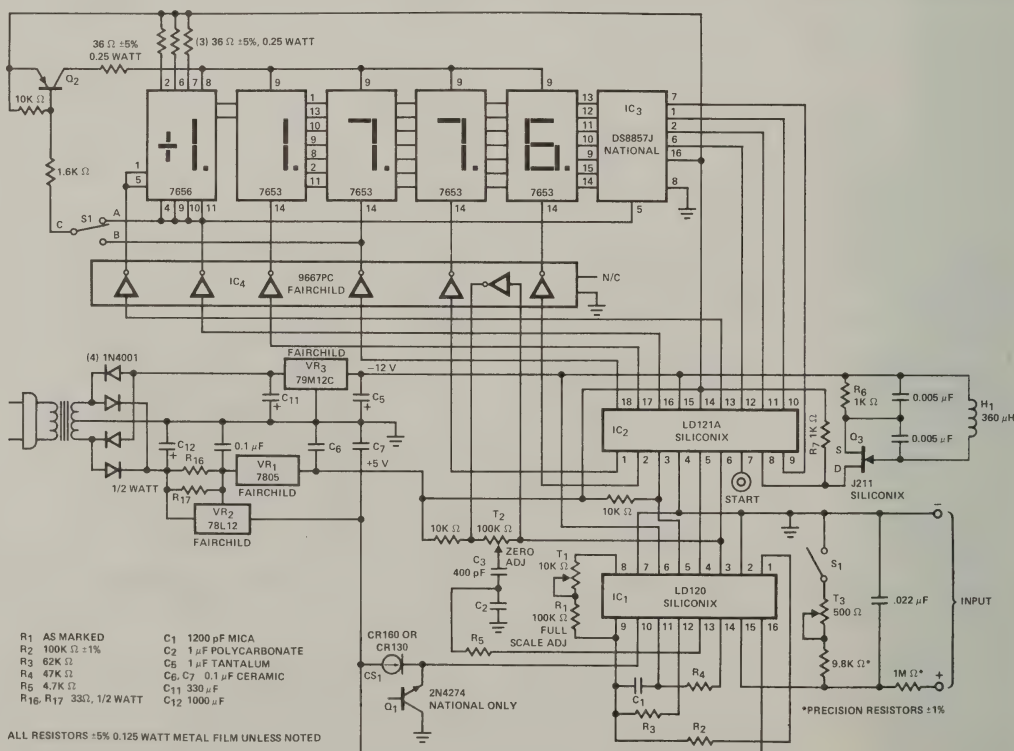
## INTRODUCTION

The 4 1/2 Digit AC powered DVM schematic, P.C. board layout and parts list are intended to aid and speed the evaluation of the Siliconix LD120/LD121A precision A/D converter. As all converters of this resolution are sensitive to trace layout, this pattern demonstrates proper grounding and signal protection. A switchable 100:1 input signal divider is provided to enable the demonstrator to become a useful laboratory DVM after the evaluation of the system has been completed.

The metal pattern and component placement diagram are both printed to a 1:1 scale. The component placement art is intended to be silk-screened on the top side of the board to provide easy component installation. It can, however, be used simply as a loading diagram.

The demonstrator DVM features,

- $\pm 1$  count linearity
- 0.75 count LSD count stability (2 V scale)
- $1\text{M}\Omega$  source impedance seen by converter input
- Auto Polarity
- Auto Zero cycle
- 200 mV F.S. range with:
  - less than 2 counts instability
  - $\pm 1$  count linearity
  - $10\text{ }\mu\text{V}$  resolution





## CONSTRUCTION HINTS

1. A solid line between two holes represents a jumper wire.
2. A copper dot is placed by pin one of the IC's.
3. The dotted area denotes the power supply. If bench power supplies are available, connect to the pads marked +15 and -15. The positive source must supply 300 mA. The negative source must supply 30 mA.
4. The tab of the CR160 aligns to + mark.
5. The LD120 should be socket mounted.
6. The 2N4274 voltage reference must be selected for a reference voltage equal to or greater than 6.6 V. A 6.6 V to 6.8 V zener reference may be substituted.
7. The CR160 current source may be replaced with a 36K  $\Omega$  resistor. Some degradation in stability and gain tempo may result.
8. The display board may be directly soldered to the circuit board, eliminating the edge connector.
9. C<sub>3</sub> is a mica dielectric.  
C<sub>1</sub> may be mica or polycarbonate dielectric.  
C<sub>2</sub>, and C<sub>6</sub> may be mylar or polycarbonate dielectric.  
C<sub>10</sub> is tantalum dielectric.  
C<sub>11</sub> and C<sub>12</sub> are electrolytic dielectric.  
C<sub>4</sub>, C<sub>5</sub>, C<sub>7</sub>, C<sub>8</sub> and C<sub>9</sub> are ceramic disc capacitors.
10. All resistors are  $\pm 5\%$  metal film unless otherwise noted.
11. Regulators VR<sub>1</sub> and VR<sub>2</sub> operate too hot to touch  $\approx (85^\circ\text{C}$  or  $185^\circ\text{F})$
12. Total power dissipation is 6 watts.
13. Break off steel screw tab from transformer nearest analog input. Connect other tab to earth ground wire from the power cord.
14. CLEAN BOARD THOROUGHLY after assembly. Any salts, finger oil, or solder flux remaining in analog circuitry may allow leakage currents detrimental to high quality performance.
15. LED displays are intensity coded. To avoid an unattractive display, check these codes for uniformity.

## LAYOUT PRECAUTIONS

The following layout precautions have been taken and should be observed on the user's P.C. board:

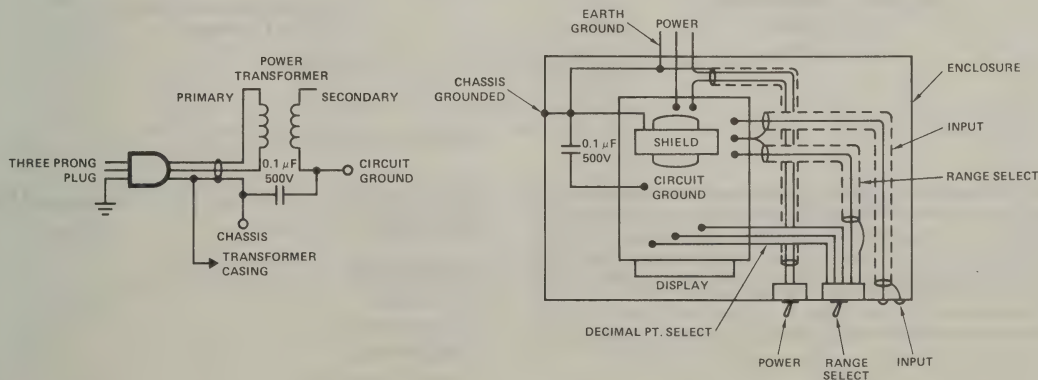
1. V<sub>IN</sub><sup>(+)</sup> trace is adjacent to ground only.
2. Traces from LD120 pins 9, 13, 15 are not adjacent to signal traces carrying AC signals.
3. U/D and comp. signals (LD120 pins 4 and 5) are separated by digital ground.
4. Digital circuitry ground paths return to the transformer (or power supply) via a different path than analog grounds from LD120.
5. The path from V<sup>(-)</sup> input to Hi-Quality ground (pin 2) does not carry any other currents.
6. The ground path from the reference and CSTRG (C<sub>2</sub>) travel directly to Analog Ground (pin 7 of LD120).
7. Int Input (LD120, pin 9) node connections are kept short and compact. This node has a relatively high impedance and is therefore subject to AC line noise pick up.
8. The +5 V supply to the LD121A should not share a current path with the display currents.

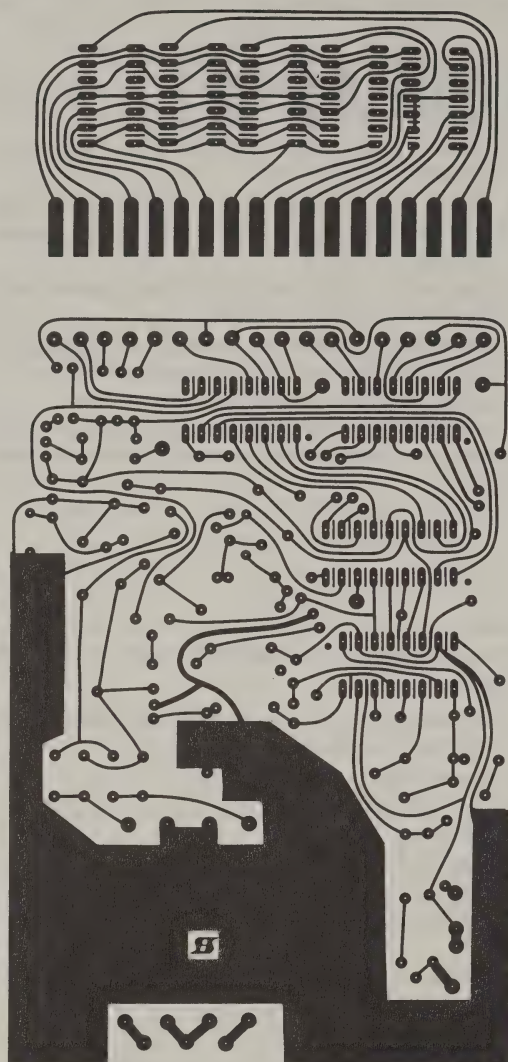
## AC SHIELDING

Improper AC shielding will result in excessive LSD run around. Therefore, the following precautions should be taken:

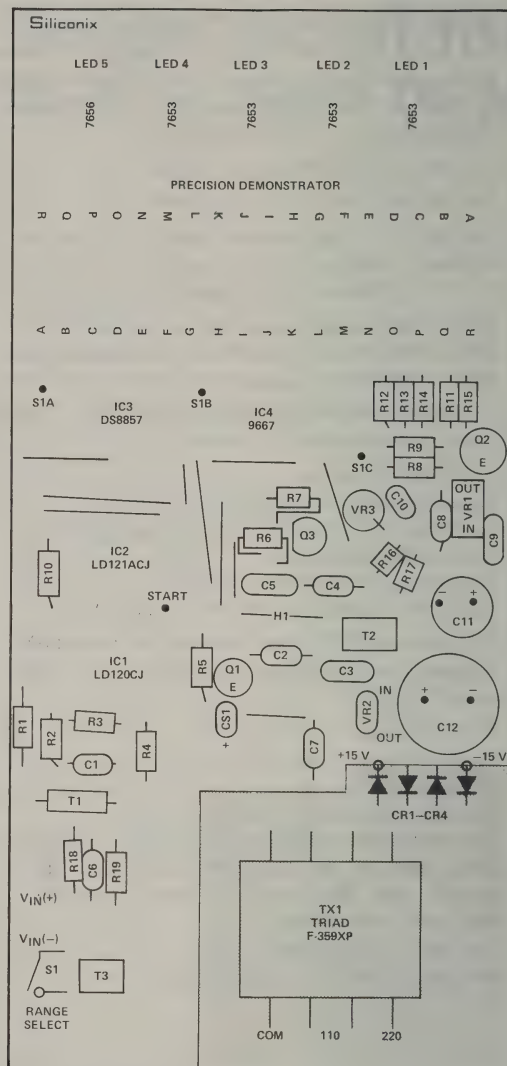
1. Use coaxial wire for the input and range select leads to the chassis front panel.
2. Enclose DVM in a metal enclosure.
3. Keep decimal point select wires separated from the input leads.
4. Keep AC line cord enclosed in box to a minimum and close to the chassis.
5. Shield the power switch leads with earth ground.

The diagram below illustrates good packaging practice:





Metal Pattern for DVM Board  
(Bottom View)



Component Placement Diagram  
(Top View)

(refer to last page of design aid for 1:1 P.C. pattern)

CAUTION: The AC line voltages associated with this board can be fatal. Proper precautions for operating this instrument must be observed by the user! Siliconix assumes no liability for unsafe operation.

### FABRICATION HINTS

All holes require a #60 drill except for the following holes which require a #54 drill:

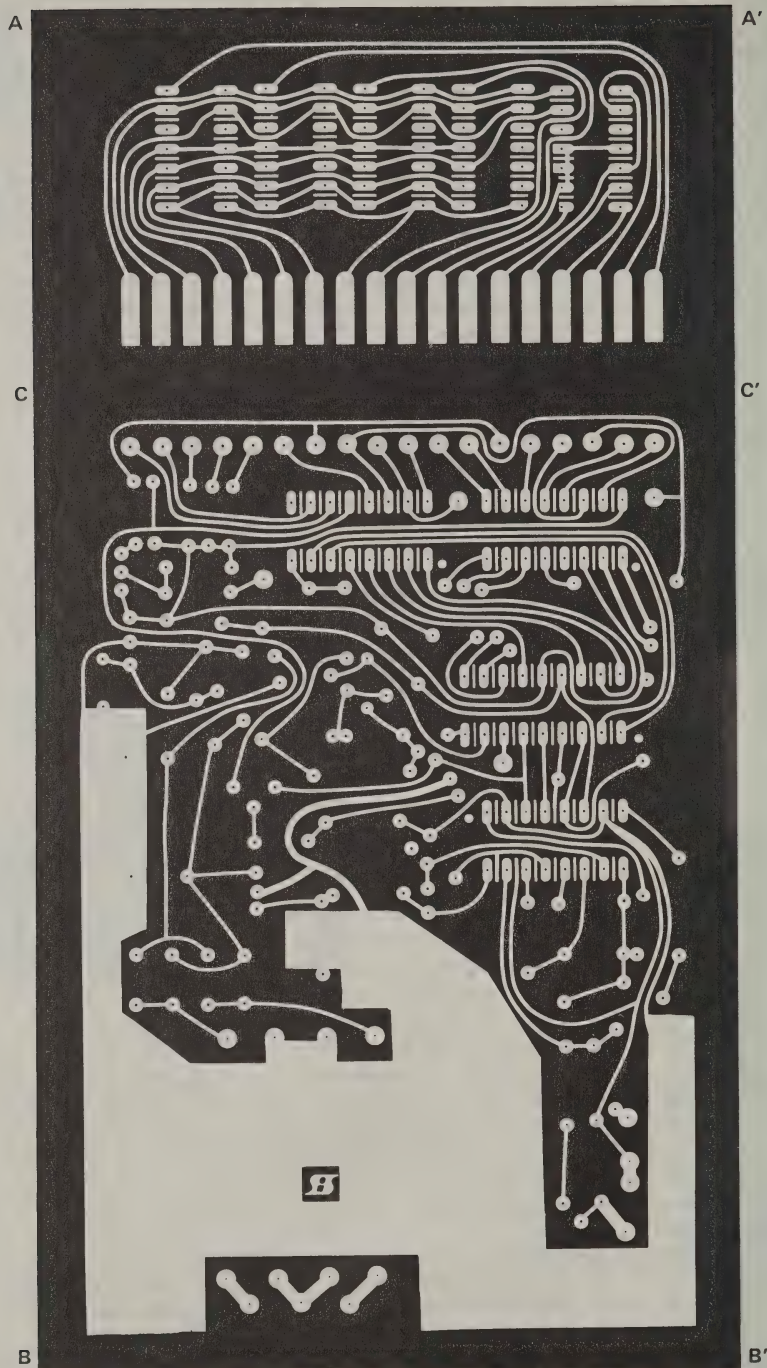
- Transformer
- AC inputs
- Edge connector
- V<sub>IN</sub> (+ and -)
- Range control pins
- Decimal point select

Part Numbers	Quantity	Description	Recommended Manufacturer and Part Number
IC1	1	Analog Processor IC	Siliconix LD120CJ
IC2	1	Digital Processor IC	Siliconix LD121ACJ
IC3	1	Display Decoder/Driver	National DS8857J
IC4	1	Seven Buffer/Driver	Fairchild 9667PC
LED 1-4	4	Seven Segment 0.43" LED Display	Hewlett-Packard 5082-7653
LED 5	1	±1 Overflow 0.43" LED Display	Hewlett-Packard 5082-7656
VR1	1	+5 V Voltage Regulator	Fairchild $\mu$ A7805UC
VR2	1	+12 V Voltage Regulator	Fairchild $\mu$ A78L12AWC
VR3	1	-12 V Voltage Regulator	Fairchild $\mu$ A79M12HC
Q1	1	NPN Transistor	National (Only) 2N4274
Q2	1	PNP Transistor	Motorola 2N4402
Q3	1	N-Channel JFET	Siliconix J211
CS1	1	1.3 or 1.6 mA Current Source	Siliconix CR130 or CR160
H1	1	360 $\mu$ H Inductor $\pm 5\%$	—
S1	1	DPDT Miniature Toggle Switch	C & K 7201
S2	1	SPST Miniature Toggle Switch	C & K 7101
C1	1	1200 pF Mica Capacitor	—
C2	1	1 $\mu$ F Polycarbonate Stocked Foil Cap.	Siemens B32 541-1.00/5/100
C3	1	400 pF Mica Capacitor	—
C4	1	.0047 $\mu$ F Mylar Capacitor	Sprague 192P4729R8
C5	1	.047 $\mu$ F Mylar Capacitor	Sprague 192P504739R8
C6	1	.022 $\mu$ F Mylar Capacitor	Sprague 192P2239R8
C7-9	3	0.1 $\mu$ F Ceramic Disc Capacitor	—
C10	1	1.2 $\mu$ F Tantalum Cap — 10 V	Sprague 198D125X90225H1
C11	1	330 $\mu$ F Electrolytic Cap — 25 V Radial Lead	Mallory VTT330J25
C12	1	1000 $\mu$ F Electrolytic Cap — 25 V Radial Lead	Mallory VTT1000M25
T1	1	5K $\Omega$ Multiturn Trimpot	Spectrol 43P502
T2	1	100K $\Omega$ Multiturn Trimpot	Spectrol 64Y104
T3	1	500 $\Omega$ Multiturn Trimpot	Spectrol 64Y501
—	2	Bannana Jacks	—
R1-2	2	100K $\Omega$ $\pm 1\%$ , 1/8 Watt Resistor	—
R3	1	62K $\Omega$ $\pm 5\%$ , 1/8 Watt Resistor	Allen Bradley
R4	1	47K $\Omega$ $\pm 5\%$ , 1/8 Watt Resistor	Allen Bradley
R5	1	4.7K $\Omega$ $\pm 5\%$ , 1/8 Watt Resistor	Allen Bradley
R6, R7	2	1K $\Omega$ $\pm 5\%$ , 1/8 Watt Resistor	Allen Bradley
R8	1	1.6K $\Omega$ $\pm 5\%$ , 1/8 Watt Resistor	Allen Bradley
R9-11	3	10K $\Omega$ $\pm 5\%$ , 1/8 Watt Resistor	Allen Bradley
R12-15	4	36 $\Omega$ $\pm 5\%$ , 1/4 Watt Carbon Comp.	Allen Bradley
R16-17	2	33 $\Omega$ $\pm 5\%$ , 1/2 Watt Carbon Comp.	Allen Bradley
R18	1	1M $\Omega$ $\pm 1\%$ , 1/8 Watt Wire Wound	—
R19	1	9760 $\Omega$ $\pm 1\%$ , 1/8 Watt Wire Wound	—
AC Power Supply Parts			
TX 1	1	24 V C.T. Transformer	TRIAD F-359XP
CR1-4	4	Rectifier Diodes	Motorola IN4002
—	1	3-Wire Power Cord w/Plug	—



Metal Pattern

Scale 1:1

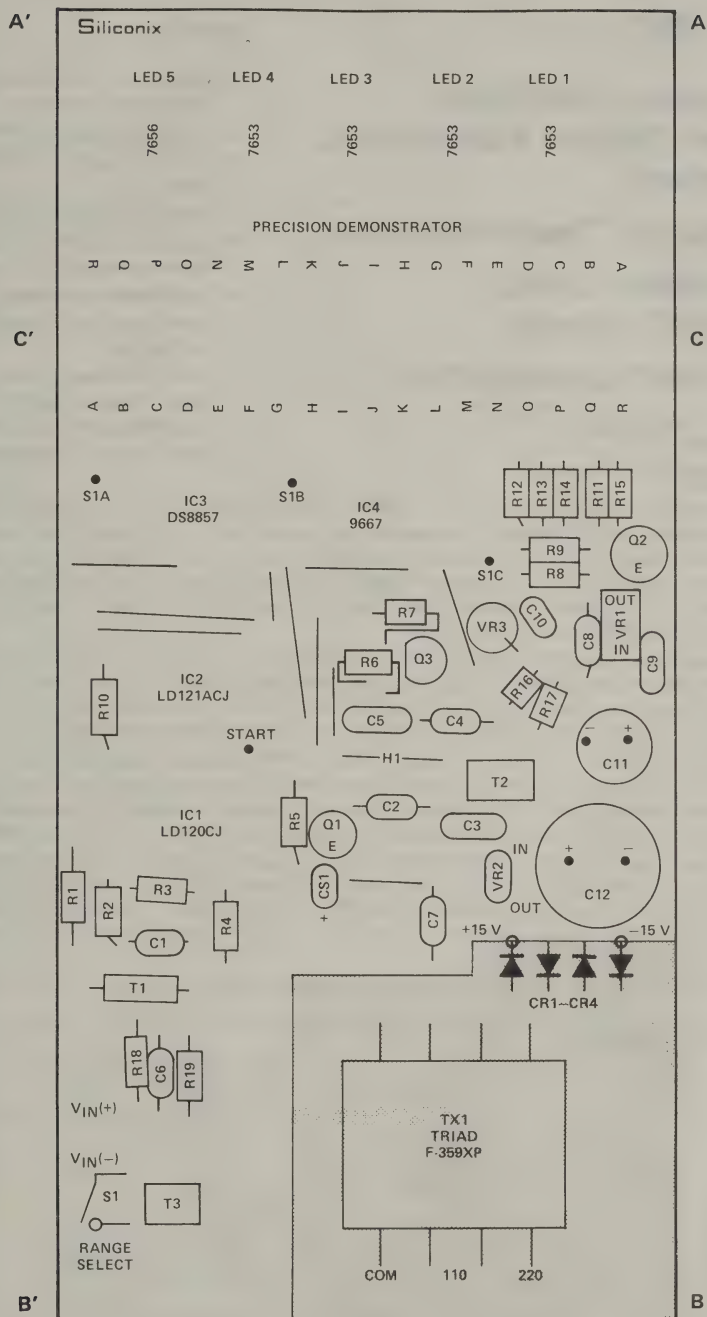


LD120/LD121A 4 1/2 Digit DVM



## Component Placement Diagram

Scale 1:1



LD120/LD121A 4 1/2 Digit DVM

# 4½ Digit A/D Converter Set designed for . . .



- **High Accuracy and High Resolution Digital Voltmeters, Panel Meters**
- **Digital Scales, Thermometers**
- **Microprocessor Data Acquisition Systems**
- **Scientific Instrumentation**

## BENEFITS

- 0.005%  $\pm 1$  Count Accuracy, Ensures High System Performance
- 1  $\mu\text{V}$  Resolution for 20 mV Full Scale
- 28,500 Count Maximum for 142% Overrange
- Sample Rate from One to Five/Second
- Auto-Zero Cycle Nulls Out Internal and External Amplifier Offsets
- Auto-Polarity Operation with One Reference
- Multiplexed BCD Output for Easy Interface to Displays
- Two Overrange Outputs, Underrange Output, Blink Inhibit, and Convert-On-Command Capabilities Allow Easy Interface to External Circuitry and Microprocessors

## DESCRIPTION

Replace LD121 with LD121A  
for New Designs

The LD122/LD121A 4½ digit A/D system uses Siliconix's "Quantized Feedback" conversion technique. Intrinsic features of this system are Auto-Polarity, Auto-Zero and ratiometric operation. No critical components are required except for a stable voltage reference and a low noise op amp. The technique offers superior linearity, normal mode rejection, and stability due to the simultaneous integration of the unknown input and the reference voltages. Unlike other conversion techniques, the integrator output voltage never represents more than 100 counts, thus critical, high resolution performance is not required of either the integrator or comparator.

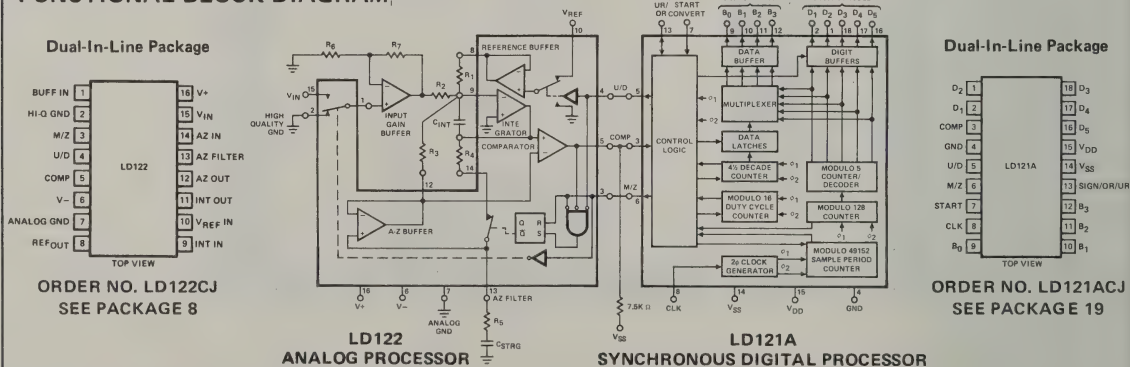
The LD122/LD121A combination extends system resolution beyond the 10  $\mu\text{V}$  maximum available from the LD120/121A system. By adding a user selected low noise input gain amplifier, and appropriate input filter, any input resolution can be achieved. Otherwise functional operation is identical to the LD120/LD121A. Complete LD122/LD121A functional information may be obtained by consulting the LD120/LD121A data sheet. Also see AN80-8 and AN77-1 application notes.

The LD122 analog processor is fabricated with a unique combined PMOS/Bipolar process. It contains all the necessary amplifiers, MOSFET switches, and switch driver circuits for the system. The reference voltage input is fully buffered on the LD122 to eliminate the reference switch resistance as a source of error. All the amplifiers are internally compensated. The LD122 directly interfaces the LD121A digital processor with no additional active components required.

The LD121A synchronous processor contains all the digital circuitry for the quantized feedback system. Device outputs supply two overrange signals, underrange, sign and 4½ digits of multiplexed BCD data. (All outputs are TTL compatible.) Overrange is also indicated by blinking digit strobes above 20,000 counts. An input is provided to inhibit this feature at user option. Microprocessor controlled operation is simplified by a start conversion input that allows conversion-on-command.

Both devices are supplied in space saving 300 mil dual-in-line packages. The LD122 has 16 pins and the LD121A has 18 pins.

## FUNCTIONAL BLOCK DIAGRAM



## ABSOLUTE MAXIMUM RATINGS

$V_{IN}$ (Pin 15, 2 LD122) . . . . .	$V_- < V_{IN} < V_+$
$V_+ - V_-$ (LD122) . . . . .	32 V
$V_{SS} - V_{DD}$ (LD121A) . . . . .	20 V
Any Pin (LD121A) . . . . .	$V_{DD}$ to $V_{SS} \pm 0.3$
$V_{REF}$ . . . . .	+V

Operating Temperature . . . . .	0 to 70°C
Storage Temperature . . . . .	-65 to 125°C
Power Dissipation (Package)* . . . . .	750 mW

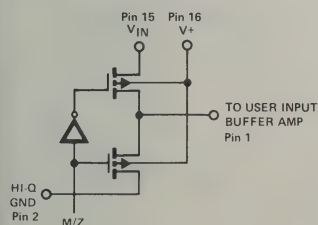
\* Device mounted with all leads welded or soldered to PC Board. Derated 6.3 mW/°C above 25°C.

## ELECTRICAL CHARACTERISTICS

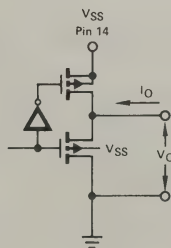
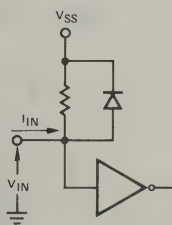
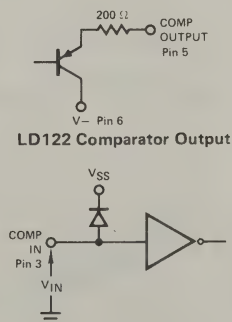
All DC parameters are 100% tested at 25°C. Lots are sample tested for AC parameters and high and low temperature limits to assure conformance with specifications.

CHARACTERISTIC				MIN	TYP	MAX	UNITS	TEST CONDITIONS UNLESS NOTED OTHERWISE V+ = 12 V; V- = VDD = -12 V, VSS = 5 V, TA = 25°C	
1	SYSTEM (Notes 2 and 3)		Linearity	1	±1/4	1	Count	2 V Scale	
				2	±1/2	2		200 mV Scale	
2			Noise (Note 1)		1/3	1	Count	2 V Scale	
				1/2	2	200 mV Scale			
3		NMRR		40		dB	fL = 50 or 60 Hz		
	PSRR		80						
4		Gain T.C.		5	15	ppm/°C			
5		Zero Drift		1	5	Count	TA = 25 to 75°C, CSTRG = 1 μF, RIN ≤ 100K Ω		
6	LD121A C C J DIGITAL	POWER	VSS	4.5	5	5.5	V	Range Over Which Functionality is Guaranteed	
7			VDD	-10.8	12	-13.2			
8			ISS	(Note 4)		14	25	mA	
9			IDD		-14	-25			
10		INPUTS	VINH	Comparator Input, Sign/UR/OR/ Blink (Note 5), Start, CLK IN	4.0			V	Guaranteed Input Threshold Voltages
11			VINL				0.5		
12			IINH	Sign/OR/UR (Note 5)		170	300	μA	VIN = 5 V
13			IINL	Start Convert, Clock		-150	-400		VIN = 0 V
14		OUTPUTS	VOH	Bit Lines, Sign/OR/UR Digit Strobes	2.4			V	I OH = -40 μA
15			VOL				0.6		I OL = 1.6 mA
16			VOH	M/Z	4.0				I OH = -150 μA
17			VOL				0.6		I OL = 0.8 mA
18			VOH	U/D	4.0				I OH = -0.5 mA
19			VOL				0.6		I OL = 0.8 mA
20		DYN	tp	Start Convert (Note 6)	20			μs	
21			fCLK		50		250	kHz	50% Duty Cycle
22				Rep Rate (Strobes)	78		470	Hz	fCLK ÷ 640

## INPUT/OUTPUT SCHEMATICS



LD122 Input

LD121A Output Buffers  
(Digits, Bits, Sign, M/Z U/D)LD121A Clock Input  
Start Convert

LD122 Comparator Output

LD121A Comparator Input

## ELECTRICAL CHARACTERISTICS (Cont'd)

CHARACTERISTIC				MIN	TYP	MAX	UNITS	TEST CONDITIONS UNLESS NOTED OTHERWISE $V_+ = 12\text{ V}$ ; $V_- = V_{DD} = -12\text{ V}$ , $V_{SS} = 5\text{ V}$ , $T_A = 25^\circ\text{C}$
23	POWER	$V_+$		9	12	15	V	
24		$V_-$		-9	-12	-15		
25		$I_+$				3.5	mA	
26		$I_-$				-3		
27	INPUT SWITCH	$I_{GND}$		0		-2	mA	M/Z, U/D = 2.4 V
28		$V_A$	(Note 7)	-3		+3	V	
29		$r_{DS(on)}$	On Resistance, $V_{IN}$ or Hi-Q Switches			5.5	$k\Omega$	$V_A = +1\text{ V}$
30						8.0		$V_A = -1\text{ V}$
31	LEAKAGE	$I_{LEAKAGE}$	Leakage Current, Switch ON or OFF		2		pA	$V_A = \pm 2.8\text{ V}$
32								
33								
34								
34	AZ	$I_{SOURCE}$			-100		$\mu\text{A}$	
35		$I_{SINK}$			800			
36		$I_{STRG}$			100		pA	$T_A = 70^\circ\text{C}$
37		$V_{OFFSET}$		-50		50	mV	$V_{OUT} = 0\text{ V}$
38	REF		Switch Resistance (on) (Note 8)		6	20	$k\Omega$	$V_{STRG} = -4\text{ V}$ , $I_{DS} = 30\text{ }\mu\text{A}$
39		$I_{SOURCE}$	Pin 8	-400	-800		$\mu\text{A}$	$V_{IL} (U/D\text{ IN}) = 0.8\text{ V}$ , $V_O = 0\text{ V}$
40		$I_{SINK}$	Pin 8		100			$V_{IH} (U/D\text{ IN}) = 2.0\text{ V}$ , $V_O = 2\text{ V}$
41		$I_{SOURCE}$	(Note 9)	-50	-100		$\mu\text{A}$	$V_{IN} (\text{Int. IN}) = -100\text{ mV}$ , $V_O = 0\text{ V}$
42	INT	$I_{SINK}$		400	800			$V_{IN} (\text{Int. IN}) = 100\text{ mV}$ , $V_O = 0\text{ V}$
43			Output Swing	-10		10	V	
44		$V_{OUT}$		-5			V	$R_L = 10k$ to $+5\text{ V}$ , AZ FILTER IN = 100 mV
45		$V_{OFFSET}$			:5		mV	INTEGRATOR OUT = 0 V
46		$I_{IH}$	M/Z, U/D Inputs			20	$\mu\text{A}$	$V_{IH} = 2.0\text{ V}$
47		$I_{IL}$				-100	$\mu\text{A}$	$V_{IL} = 0.8\text{ V}$

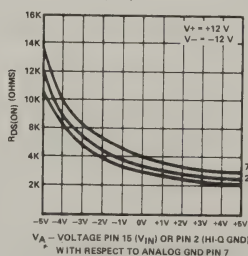
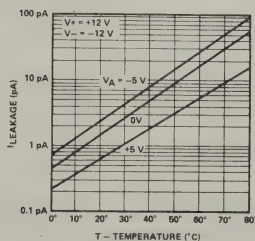
Typical values are for Design Aid Only, not guaranteed and not subject to production testing.

LD122 - CMAM-C LD121A - IPDC VI

## NOTES:

1. Bit width over which reading is stable 95% of the time.
2. System Parameters are not directly tested.
3.  $f_{CLK} = 163.84\text{ kHz}$ ,  $V_{REF} = 6.8\text{ V}$ .
4. All outputs disconnected.
5. Pin characteristic only during  $D_4$  strobe time.
6. Minimum positive going pulse width to initiate a conversion.
7. Maximum voltage range for  $V_{INPUT}$  (pin 1) or hi-quality GND (pin 2).
8.  $V_{STRG}$  must be more positive than  $-4$  volts.
9. Reference Source Impedance must be less than  $10K\ \Omega$ .

## TYPICAL CHARACTERISTICS

 $V_{IN}$  and  $V_{Hi-Q}$  GND SwitchesTypical  $r_{DS(on)}$  vs  $V_A$  and TempTypical Input Leakage vs Temp and  $V_A$ 

Input Leakage Test Set-up

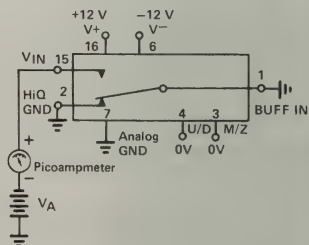


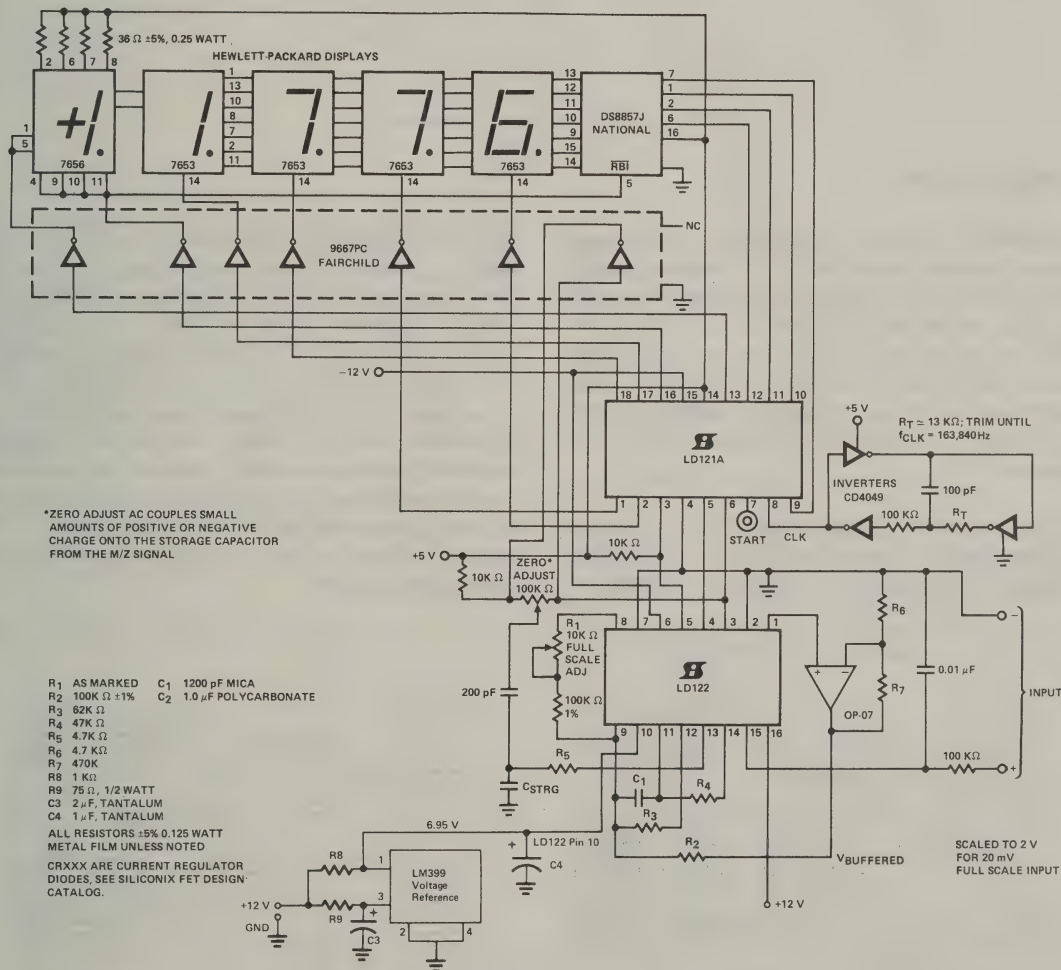


Figure 1 shows the arrangement for a 20 mV full scale,  $1\ \mu\text{V}$  resolution DVM. The OP-07 provides the necessary low noise operation to achieve stable  $1\ \mu\text{V}$  readouts. Proper layout is necessary for the LD122 and OP-07 front end circuitry to reduce stray RF and hum pickup. Having the OP-07 included in the Auto-zero loop cancels front end amplifier bias-offsets, and more important drift with temperature. Reference drift is reduced by using an LM399 precision voltage reference with built in heater.

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### CIRCUIT BENEFITS

- $1\ \mu\text{V}$  Resolution
- Overrange Blinking
- $0 \rightarrow 19,999\ \text{mV}$  Input Voltages
- Zero Adjust to Null Offset Introduced by PC Board Leakages and Comparator



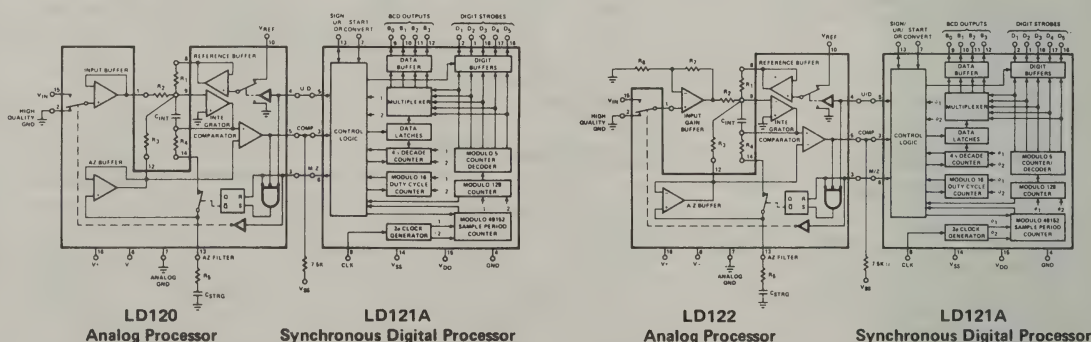
# Function/Application of the LD122/LD121A $\pm 4\frac{1}{2}$ Digit A/D Converter Set in Measurement Systems

## INTRODUCTION

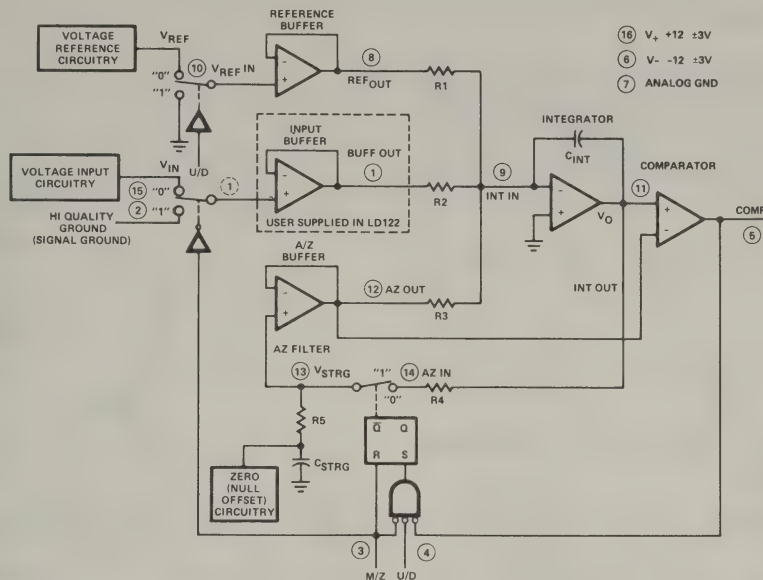
The Siliconix LD122/LD121A combination extends system resolution capability beyond the  $10\ \mu\text{V}$  maximum possible with the LD120/LD121A to literally the state of the art in low noise op-amps. All the while however, retaining the features of the LD120/LD121A system such as  $4\frac{1}{2}$  digit precision, Auto-Polarity, Auto-Zero and ratiometric operation. Typical low voltage measurement applications of the LD122 include thermocouples, resistance bridges, and strain gauges.

As the functional block diagrams show in Figure 1, the two A/D converters are identical except for the input gain buffer which is user supplied in the LD122. Although it's

theoretically possible to manipulate the LD120 resistor ratios to accommodate any input voltage range, the  $1/f$  noise characteristics of the LD120 unity input PMOS buffer make it impossible to obtain better than  $10\ \mu\text{V}/\text{LSB}$  resolution capability. A  $10\ \mu\text{V}/\text{LSB}$  resolution capability corresponds to a 200 mV fullscale range. However by using an external op-amp with good noise characteristics as diagrammed with the LD122, low voltage resolution capability becomes essentially a function of the external op-amp's performance. For instance it's currently possible to obtain op-amps with noise levels on the order of  $1\ \mu\text{V}$ , enabling our system to have  $1\ \mu\text{V}/\text{LSB}$  (or 20 mV full scale) measurement capability.



Switch States are for a Logic "0" at U/D and M/Z Inputs  
Figure 1



Analog Processor Expansion Diagram  
Figure 2

Since the LD122/LD121A converter is essentially a LD120/LD121A system suitably modified (in Figure 2) and numerous dissertations on the quantized feedback technique can be found in the Siliconix LSI Data Book, discussion of basic converter operation will be foregone in favor of specific precautions, guidelines and applications to follow when doing very low voltage measurements. For those desiring basic operational information I refer you to the LD120/LD121A data sheet and application note AN77-1.

## APPLICATIONS INFORMATION

### Features and Applications

With its long list of high performance features:

- Wide choice of input voltage ranges
- High resolution 4½ digit operation
- 0.005% ± 1 count accuracy
- Highly linear operation with simultaneous unknown-reference integration
- Auto Polarity operation with only 1 external reference
- Fully buffered inputs
- TTL output drive
- Automatic Zeroing cycle

Applications Tailor Made for the LD122/LD121A include:

- Microvolt Digital Volt Meters
- Thermocouple Temperature Measurement Systems
- High Precision strain gauge measurement systems
- Scientific Instrumentation and others

### LD122-LD120 Similarities

Probably the best way to think of the LD122 is as if it were an LD120 with the  $V_{IN}$  input amplified. So anywhere you see an expression for the differential LD120 input ( $V_{IN}-V_{HI-Q}$ ) substitute  $X(V_{IN}-V_{HI-Q})$  where  $X$  is the gain of the user supplied input buffer. Doing so, our A/D output count relation becomes:

$$\text{Output Count} = \frac{X(V_{IN}-V_{HI-Q})}{V_{REF}} \cdot \frac{R1}{R2} \cdot 65,536$$

Now in addition to being able to scale the converter for different input ranges by changing the  $R1/R2$  ratio, we can also alter the input buffer gain =  $X$ .

Figure 3 shows a typical application of the LD122/LD121A chip set. The system is set up to indicate full scale if 2V (100  $\mu\text{V}/\text{LSB}$ ) is applied to  $R2$  by the input gain buffer. However the input gain  $X$  is 100 so that a 20mV (1 $\mu\text{V}/\text{LSB}$ ) signal applied to the input buffer results in a fullscale reading. If the input gain were only 10, then a 200mV (10 $\mu\text{V}/\text{LSB}$ ) signal would be necessary to cause a full scale reading.

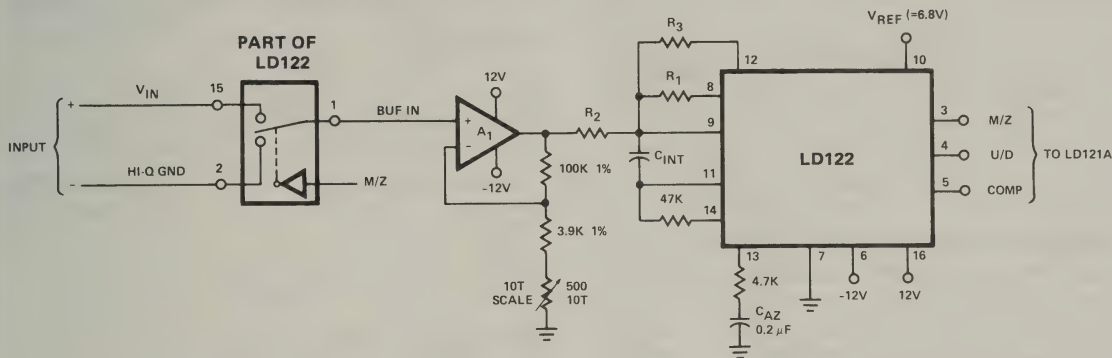




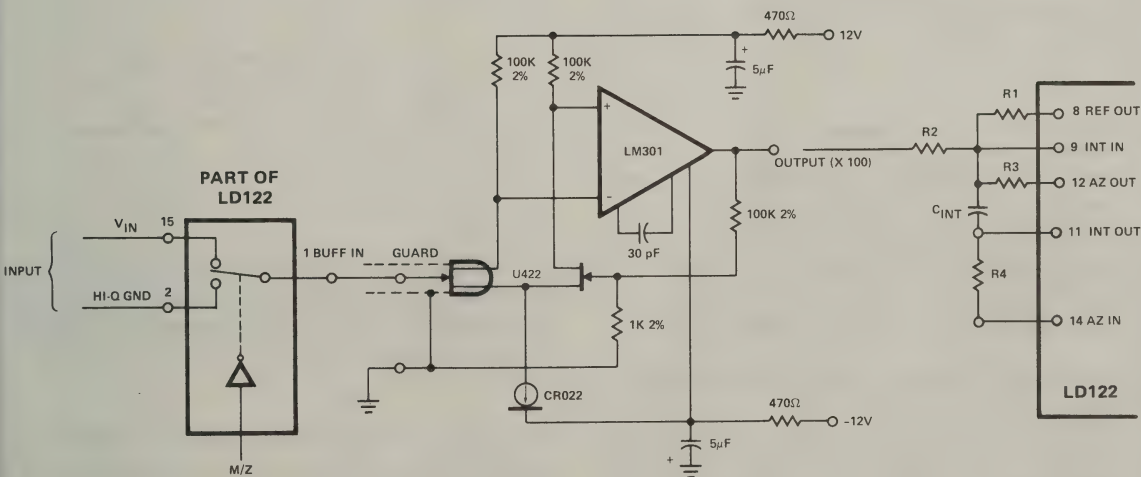
## Input Gain Buffers

Figure 5 shows the arrangement for a 20 mV full-scale front end. If an extremely low source impedance were used, such as thermocouple, then an amplifier such as the LM201A could be used for  $A_1$ . For higher impedances, lower bias currents are required until at about  $1K \Omega$  or above, a JFET amplifier will be required. Note that MOS input op-amps are not quiet enough.

Even the BI-FET op-amps are only good for a  $20K \Omega$  input resistance up to  $75^\circ C$ . The circuit of Figure 6 has an input leakage of only 2 pA typical at  $75^\circ C$  and would be usable with  $1M \Omega$  input resistance. Although not covered here, there are ways to reduce leakage effects over temperature by a factor approaching 10.



20 mV F.S. Meter (Front End)  
Figure 5



Ultra-Low-Leakage Preamp  
Figure 6

## Input Buffer Selection Considerations

Ideally we would like the user supplied input buffer to have constant gain over the entire input voltage range so that the converter's linearity and accuracy can be preserved. Unfortunately real life op-amp characteristics, principally common mode voltage, prohibit such an ideal situation and must be reckoned with when choosing an op-amp.

Consider first of all the following unity gain voltage follower configuration in Figure 7.

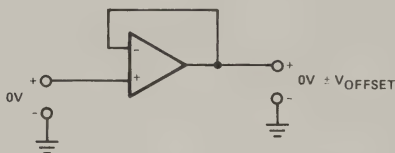


Figure 7

With an ideal op-amp, inputting 0V should give us a 0V output. With a real amplifier though, there is a small error offset  $V_{\text{OFFSET}}$  present as shown. Assuming that this offset is constant over the entire input voltage range, it is easily taken care of by the LD122 in the Auto-Zero interval where such error offsets are easily corrected for.

Suppose that we now input a 20 mV signal to our unity buffer. See Figure 8.

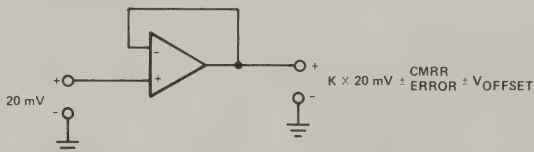


Figure 8

If our circuit is ideal, then  $K=1$  for a unity gain. Realistically though, it's slightly less than 1, so just considering our voltage gain (no other errors) we don't quite get a 20 mV output. Such a loss in gain means that we don't quite get the output range that we'd like from our A/D when a full scale input voltage is applied.

This gain loss, if constant, is easily corrected for by slightly trimming the LD122  $R_1/R_2$  ratio for a full scale reading with a full scale voltage input. The one error that we cannot compensate for however, is the common mode error, CMRR, which is non-linear and varies depending on the input-voltage. This being the case, we'd like the maximum error attributable to CMRR to be less than 1 count of the A/D. If we were using the above buffer with an LD122/LD121A to measure down to  $1 \mu\text{V}/(\text{count or LSB})$  (20 mV range) then the maximum CMRR error must be less than  $1 \mu\text{V}$ .

If we now use a buffer with a gain of 100 as diagrammed in Figure 9, a full scale input (20 mV) to the buffer will result in a 2 volt output signal. Since we would like to resolve to 1 part in 20,000 ( $1 \mu\text{V}$  input,  $100 \mu\text{V}$  output) the output

CMRR error must be less than  $\frac{1}{20,000} \cdot 2\text{V}$  (i.e. for  $\pm 1$  count operation CMRR better than 86 dB over the input voltage range) or  $100 \mu\text{V}$  over the entire voltage range. If noise is significant, (thermal, junction, etc.) the sum of CMRR error and noise must be less than  $\left[ \frac{1}{20,000} \times \text{output buffer voltage} \right]$  for  $\pm 1$  count resolution.

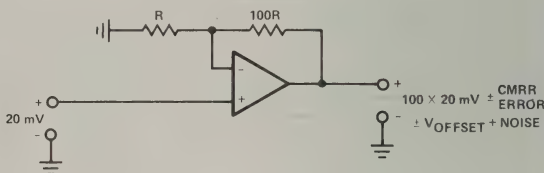


Figure 9

## System Layout Guidelines and Precautions

When operating in the microvolt region extreme care must be taken with system layout and component selection, particularly in the front end, to minimize stray noise pick up. For instance the voltage inputs to the A/D should be shielded and put through a low pass filter as illustrated in Figure 10.

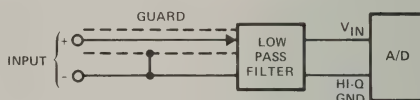


Figure 10

In laying out a printed circuit board, good layout technique should be observed with particular emphasis placed on possible problems due to grounding, capacitive coupling, leakage and thermocouple effects between pins and traces as follows.

Grounding considerations are presented in detail in Appendix B and as discussed there, minimum system noise requires that analog and digital grounds be kept separate until terminated at the power supply.

Capacitive coupling and leakage problems are particularly noticeable with the LD122 analog chip, but can be minimized through the use of a 2 sided glass-epoxy board, with guard traces driven from low impedance sources. Of foremost concern with the LD122 is capacitive coupling between pins 4 (U/D in) and 5 (COMP out) as diagrammed in the chip pin out below. As shown, a digital ground trace between pins 4 and 5 is recommended to reduce these inter-pin effects. The general rule of thumb to follow here is to guard [high impedance analog inputs and pulse width critical digital waveforms] from [voltage supplies and digital signals] by driving [the guard rings and traces] with [low impedance sources having potentials close to the guarded pins].

Following this approach it might also be wise to isolate pin 10 ( $V_{REFIN}$ ) with traces from pin 8 ( $REF_{OUT}$ ) and pin 13 (A/Z filter) with a trace from pin 12 (A/Z out) as shown in Figure 11.

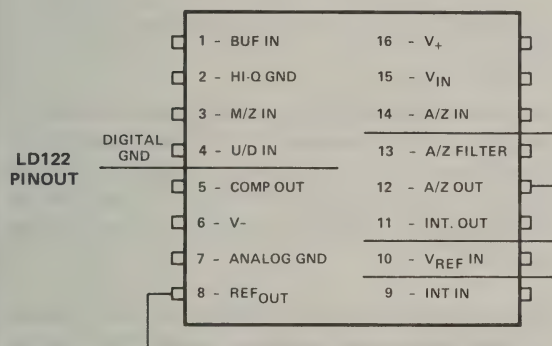


Figure 11

Down in the microvolt region ordinarily insignificant sources of noise can become major problems unless adequately accounted for in the system layout. Probably the most insidious of which are thermal effects in the form of thermocouple junctions and board temperature gradients. Recall that 2 dissimilar metals placed together form a thermocouple junction and when heated can supply a small output voltage. Even at room temperature the effects are

appreciable in the microvolt region and numerous junctions are possible on a circuit board where we go from gold plated edge connector to tin plated copper trace to solder to kovax IC lead to semiconductor interface. Board temperature gradients can effect minute resistance and thermocouple changes resulting in unequal voltage potentials and noise over even the most carefully balanced signal paths. Therefore, layout in terms of optimum package placement, minimum input lead length and minimizing temperature gradients should be considered. Generally speaking, the input gain buffer as well as any input circuitry should be electrically and thermally shielded for best results.

In any measurement application component quality and stability is always a question and a few words concerning LD122 resistor and capacitor selection are appropriate here. Ordinarily R1 and R2 quality are critical to proper circuit operation and they and any accompanying trimming components are recommended to be wirewound or metal film since carbon and oxide film resistors can generate large amounts of thermal noise.

In addition, since we are talking about gain setting resistances, they should track each other over the operational temperature range lest a gain error result.

When a user supplied input buffer of appreciable gain is used, the burden of quality becomes shifted to the input buffer components since any noise there is appreciably magnified, while R2 now faces a large input signal in relation to its possible noise contribution. The gain setting resistors must therefore be of appropriate quality. In either case, resistor quality should be appropriate to its relative noise contribution.

The integrator capacitor  $C_{INT}$  should be mylar or better quality. The autozero capacitor  $C_{STRG}$  should be mylar, polystyrene, polycarbonate, or polypropylene, the latter being best with regards to dielectric absorption. Resistors R3, R4, R5 quality is not critical, but should be long term stable. Above all, capacitive losses (leakage, dielectric absorption, etc.) must be kept to a minimum for proper operation as Appendix A explains.



# APPENDICES

## APPENDIX A: ERROR TERMS

**Zero Drift** — The main source of zero drift is leakage from the input and auto zero buffers. Figure 12 shows typical input and auto zero leakages over temperature. The error component due to  $I_{IN}$  is simply

$$\Delta V_{IN} = \Delta I_{IN} \cdot R_{SOURCE}$$

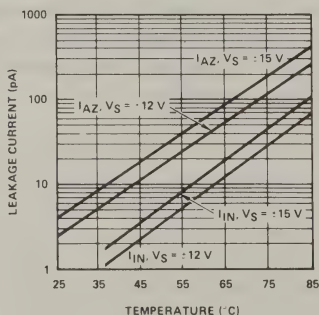
For a  $1M\ \Omega$  input resistance, and  $\Delta I_{IN} = 30\text{ pA}$  at  $75^\circ\text{C}$ ,  $\Delta V_{IN} = 30\ \mu\text{V}$ , corresponding to a 0.3 bit offset at 2 V full-scale, and 3 count offset at 200 mV full-scale. This offset can be reduced by reducing  $R_{SOURCE}$  or by inserting a compensating  $R_{SOURCE}$  between  $V_{HI-Q}$  and ground.

The drift due to  $I_{AZ}$  is independent of scale factor, and is caused by the voltage on  $C_{AZ}$  drifting during the measure interval. The magnitude of drift will be

$$\Delta V_{AZ} = \frac{I_{AZ} \cdot T_{MEASURE}}{C_{AZ}} = \frac{I_{AZ} \cdot 32,768}{C_{AZ} \cdot f_{OSC}}$$

This will cause an effective input current to the integrator of  $\Delta V_{AZ}/2R_3$ , the factor two resulting from the fact that the ramp of auto-zero drift is averaged by the algorithm. This input current due to drift is analogous to an input signal of  $\Delta V_{AZ} R_2/2R_3$ , so the count drift is

$$\Delta \text{Count} = \frac{\Delta I_{AZ}}{C_{AZ} f_{OSC} V_{REF}} \cdot \frac{R_1}{2R_3} \cdot 2.15 \times 10^9$$



Typical Leakage Over Temperature  
Figure 12

So given  $\Delta I_{AZ} = 100\text{ pA}$  when up at  $70^\circ\text{C}$ ,  $R_1 = 60K = R_3$ ,  $C_{AZ} = 0.1\ \mu\text{F}$ ,  $f_{OSC} = 150\text{KHz}$ , and  $V_{REF} = 6.2\text{ V}$ ,  $\Delta \text{Count} = 1.16$  due to  $\Delta I_{AZ}$  only.

The drift caused by thermocouple junctions on the LD120 is much less than that caused by leakages.

**Gain Drift** — Full-scale gain drift is caused mainly by changes in  $V_{REF}$ . One count in 20,000 stability per degree C is  $50\text{ ppm}/^\circ\text{C}$ , so the zener reference should have at least  $10\text{ ppm}/^\circ\text{C}$  stability and the system burned-in to reduce long term drift.

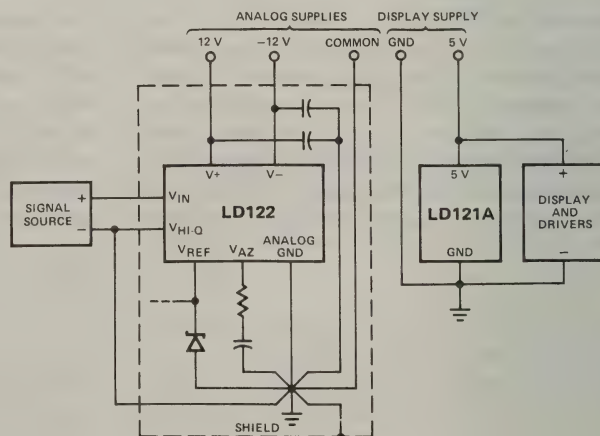
The resistors at  $R_2$  and  $R_1$  should track each other over temperature at least as well as the tempco of the reference.

## APPENDIX B

**Grounding** — The optimum ground scheme is shown in Figure 13.

The main considerations are: analog ground is common to  $V_{REF}$ ,  $C_{AZ}$ ,  $\pm 12\text{ V}$  commons,  $\pm 12\text{ V}$  bypass, ground of the signal source, common power ground, case ground; isolation of currents in the 5 V circuits from those of analog grounds; a 3-wire input connection for remote signal sources.

These connection methods will alleviate AC and DC pickup in signal inputs and integrator positive input (analog ground) from noise currents caused by the display and AC environment.



LD120/LD121A Ground System  
Figure 13



## APPENDIX C: TROUBLESHOOTING

Problem	Causes
Jittery Display	<p><math>f_{OSC}</math> is not stable (short-term)</p> <p>AC voltage on <math>V_{IN}</math>, <math>V_{HI-Q}</math>, power supplies, or <math>V_{REF}</math></p> <p>AC fields passing through unshielded circuit board</p> <p><math>R_1</math>, <math>R_2</math>, or <math>R_3</math> being carbon composition type</p> <p>Excessively small full-scale sensitivity implemented</p> <p><math>V_{AZ}</math> or <math>V_{REF}</math> too small</p> <p>Insufficient power supply bypass capacitor</p>
Offset Drift	<p>Excessive input resistance or <math>C_{AZ}</math> too small (see appendix A)</p> <p>Circuit board leakages excessive due to flux or moisture absorption</p> <p>A variable offset in grounding system</p> <p>Poor quality capacitors for <math>C_{INT}</math> or <math>C_{AZ}</math></p> <p>Sample rate too slow (<math>&lt;1</math> sec)</p> <p>Thermocouple junctions in the 200 mV range</p>
Poor Linearity	<p>Poor quality <math>C_{INT}</math></p> <p><math>V_+</math> or <math>V_-</math> less than 10 V</p> <p>Circuit board leakages to <math>C_{INT}</math></p> <p>Noise pickup on U/D or loading of U/D</p> <p><math>V_{REF}</math> modulated by display ground currents</p>
No digit strobes from LD121A	<p>Clock not functioning</p> <p>Some terminal of the LD121A more positive than <math>V_{SS}</math></p>





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Die Process & Topography	9
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## D/A CONVERTERS

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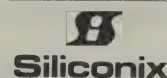
*Stresses listed under "Absolute Maximum Ratings" may be applied (one at a time) to devices without resulting in permanent damage. This is a stress rating only and not subject to production testing. Exposure to absolute maximum rating conditions for extended periods may effect device reliability.*



# D/A Converter Switches

*designed for . . .*

- 4, 10 or 14 Bit DACs
- Binary or BCD DACs
- Multiplying DACs
- Successive Approximation ADC
- Frequency Synthesizers
- Virtual Ground Switches



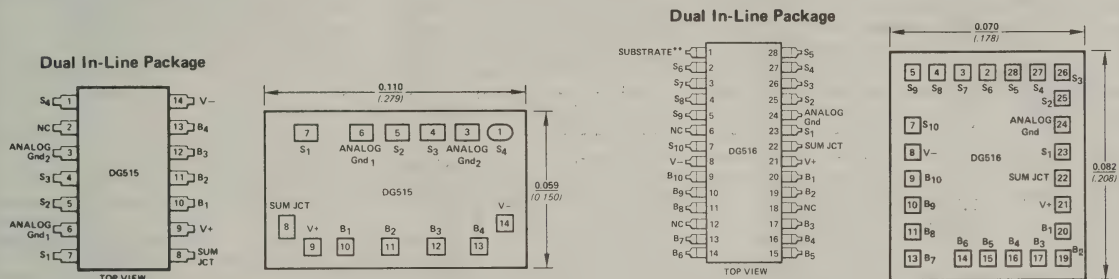
## BENEFITS

- Easily Interfaced
  - Binary Weighting of ON Resistances
- Minimizes System Power Requirements
  - 40  $\mu$ W Operating Power
- Reduces Systems Costs
  - Single Supply Operation

## DESCRIPTION

The DG515 and DG516, 4 and 10 bit SPDT switches, combine NMOS analog switches with CMOS switch drivers. These switches feature low channel ON resistance, binary weighting of ON resistance and channel resistance matching to minimize the errors that can lead to non-monotonicity in D/A converters. The binary ON resistance weighting (doubling for each bit) is continued from the DG515 to the DG516 to allow the pair to be used as a 14 bit DAC.

## PIN CONFIGURATIONS/BONDING DIAGRAMS



### ORDER NUMBERS:

DG515AP  
DG515BP  
SEE PACKAGE 11  
DG515CJ  
SEE PACKAGE 7

### \* ORDER NUMBERS:

DG515ADICE  
DG515BDICE  
DG515CDICE

### ORDER NUMBERS:

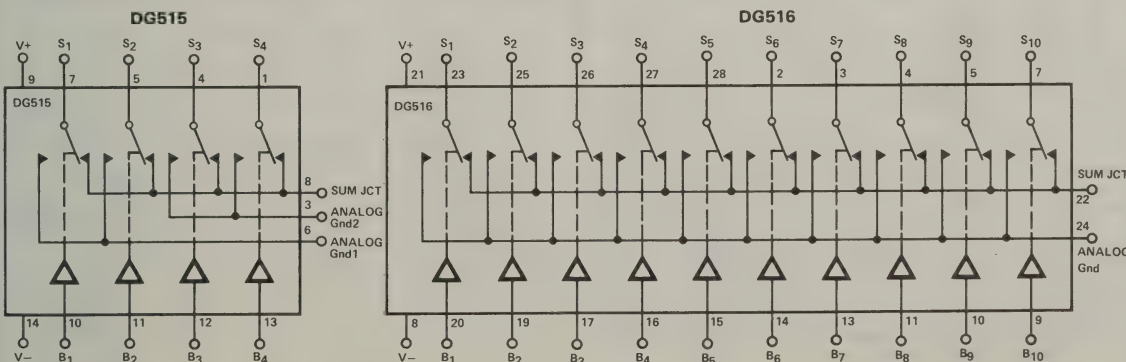
DG516AR  
DG516BR  
SEE PACKAGE 13  
DG516CJ  
SEE PACKAGE 14

### \* ORDER NUMBERS:

DG516ADICE  
DG516BDICE  
DG516CDICE

\* CONTACT FACTORY FOR TESTING AND INSPECTION CRITERIA  
\*\* SHOULD BE LEFT UNCONNECTED OR CAN BE TIED TO V<sup>+</sup>

## FUNCTIONAL DIAGRAMS



SWITCH STATES ARE FOR LOGIC "1" INPUT

DG515 DG516

8

D/A Converters

# ABSOLUTE MAXIMUM RATINGS

$V_S$ to Sum Jct or Analog Gnd	-200 mV
$V_{IN}$ (Bit Logic Input)†	$V- \leq V_{IN} \leq V+$
$I_{SWITCH}$	10 mA
Current (Any Terminal Except Switch)	30 mA
Storage Temperature (A & B Suffix)	-65 to 150°C
(C Suffix)	-65 to 125°C
Operating Temperature	
(A Suffix)	-55 to 125°C
(B Suffix)	-20 to 85°C
(C Suffix)	0 to 70°C
Power Dissipation (Package)*	
14 Pin Ceramic DIP**	825 mW
14 Pin Plastic DIP***	470 mW

28 Pin Ceramic DIP****	1200 mW
28 Pin Plastic DIP*****	625 mW
*Device mounted with all leads welded or soldered to PC board	
**Derate 11 mW/°C above 70°C	
***Derate 6.3 mW/°C above 25°C	
****Derate 10 mW/°C above 25°C	
*****Derate 8.3 mW/°C above 25°C	
†NOTE: Exceeding these voltage limits can result in a latch-up condition, excessive $I+$ and possible destruction to the device. Placing a 2K $\Omega$ resistor in series with $V+$ will protect the device and allow recovery (without power supply cycling) after the overvoltage is removed.	

# ELECTRICAL CHARACTERISTICS

All DC parameters are 100% tested at 25°C. Lots are sample tested for AC parameters to assure conformance with specifications. DICE are sorted by DC parameter tests and visual inspections.

Characteristic			DG515 Typ† @ 25°C	DG515 MAX LIMITS						DG516 Typ† @ 25°C	DG516 MAX LIMITS						Unit	Test Conditions V+ = 8.0 V, V- = 0 V
				DG515A/B			DG515C				DG516A/B			DG516C				
				-55°C To -20°C	25°C	125°C To 85°C	0°C	25°C	70°C		-55°C To -20°C	25°C	125°C To 85°C	0°C	25°C	70°C		
1	S W I T C H	rDS(on) Switch 1		6.25	6.25	9.0	7.8	7.8	11.2							Ω	IS = 10 mA	
2		rDS(on) Switch 2		12.5	12.5	18.0	15.6	15.6	22.5									
3		rDS(on) Switch 3		25.0	25.0	36.0	31.2	31.2	45.0									
4		rDS(on) Switch 4		50.0	50.0	72.0	62.5	62.5	90.0							IS = 0.1 mA		
5		rDS(on) Switch 1								100	100	144	125	125	180			
6		rDS(on) Switch 2								200	200	288	250	250	360			
7		rDS(on) Switch 3								400	400	576	500	500	720			
8		rDS(on) Switch 4								800	800	1150	1000	1000	1440			
9		rDS(on) Switch 5								1600	1600	2300	2000	2000	2880			
10		rDS(on) Switch 6–10								3200	3200	4600	4000	4000	5760			
11	ΔrDS(on) Switch to ANALG GND Switch to SUM JCT	20**							20**							%	VINH = 8.0 V, VINL = 0 V	
12	I N P U T	ID(off) IANALOG Gnd (off)		100	40		100	40		100	40	2000	100	40	2000	nA	VANALOG Gnd = 0 V, VS = -100 mV	
						2000			2000							nA	VANALOG Gnd = 0 V, VS = -20 mV	
13		ID(off) ISUMMING Junction (off)		100	40		100	40		100	40	2000	100	40	2000		VSUMMING Jct = 0 V, VS = +100 mV	
						2000			2000								VSUMMING Jct = 0 V, VS = +20 mV	
14		VIN Threshold	4.0							4.0							V	
15		IINL Input Current Input Voltage Low		-1.0	-1.0	-1.0	-1.0	-1.0	-1.0		-1.0	-1.0	-1.0	-1.0	-1.0	-1.0	μA	VINL = 0 V
16		IINH Input Current Input Voltage High		+1.0	+1.0	+1.0	+1.0	+1.0	+1.0		+1.0	+1.0	+1.0	+1.0	+1.0	+1.0	μA	VINH = 8.0 V
17		tON Turn-ON Time			120			180				120			180		ns	See Switching Time Test Circuit
18		tOFF Turn-OFF Time			170			250				170			250			
19		CD Output Capacitance ANLG GND	60							20							pF	VINL = 0 V f = 1 MHz
20	CD Output Capacitance SUM JCT	40							14									
21	CD Output Capacitance ANLG GND	40							14							pF	VINH = 8.0 V f = 1 MHz	
22	CD Output Capacitance SUM JCT	60							20									
23	I+ Positive Supply Current		5.0	5.0	150	5.0	5.0	150		5.0	5.0	150	5.0	5.0	150	μA	VINH = 8.0 V	
24	I- Negative Supply Current		-5.0	-5.0	-150	-5.0	-5.0	-150		-5.0	-5.0	-150	-5.0	-5.0	-150			
25	I+ Positive Supply Current		5.0	5.0	150	5.0	5.0	150		5.0	5.0	150	5.0	5.0	150			
26	I- Negative Supply Current		-5.0	-5.0	-150	-5.0	-5.0	-150		-5.0	-5.0	-150	-5.0	-5.0	-150			VINL = 0 V

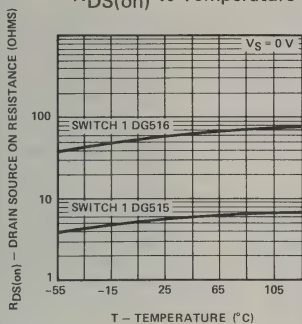
## NOTES:

- † Typical values are for Design Aid only, not guaranteed and not subject to production testing.
- \* Delta rDS(on) as percent of maximum resistance.
- \*\* This is the worst typical mismatch seen on a device.

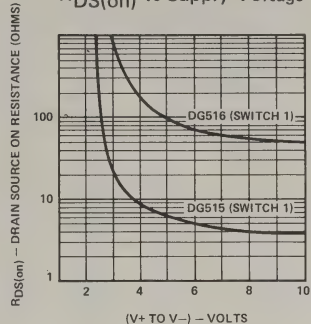
DG515-ICAS  
DG516-ICAT

# TYPICAL CHARACTERISTICS

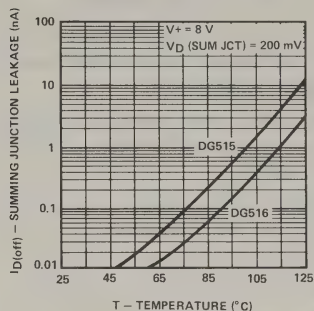
## $R_{DS(on)}$ vs Temperature



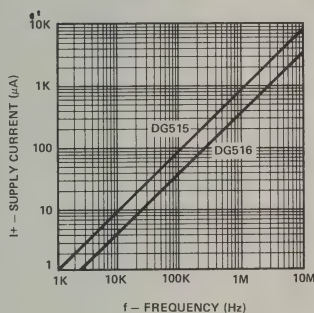
## $R_{DS(on)}$ vs Supply Voltage



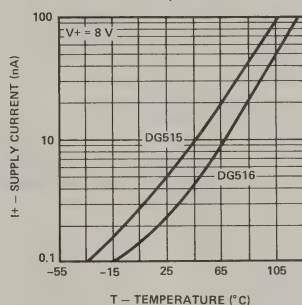
## Leakage vs Temperature



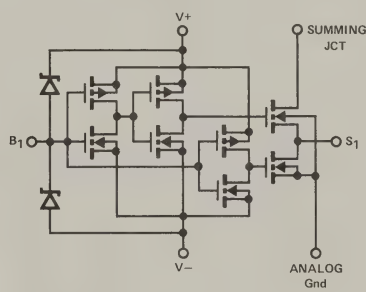
## Supply Current vs Toggling Rate



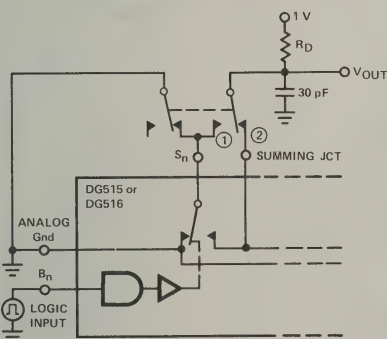
## Quiescent Supply Current vs Temperature



## Typical Channel (DG515 or DG516)

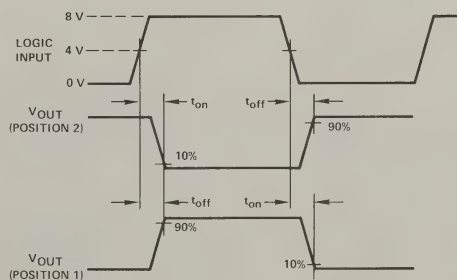


## Switching Time Test Circuit



SWITCH	$R_D$ (ohms)	
	DG515	DG516
1	50	300
2	100	300
3	200	300
4	200	510
5		510
6		1000
7		1000
8		1000
9		1000
10		1000

## Switching Test Waveforms



## APPLICATIONS

The following Application Circuits are intended to illustrate the following points:

1. A  $2K\ \Omega$  resistor should be in series with  $V_+$  to limit supply current with negative ringing of the bit inputs.
2. Temperature compensation for  $R_{DS(on)}$  can be provided in the feedback path of the Op-Amp.
3. 4 Quadrant multiplication is possible by using the Analog Gnd current.
4. Bipolar reference voltages can be used in all configurations.
5. Resistor weighting other than Binary can be used.

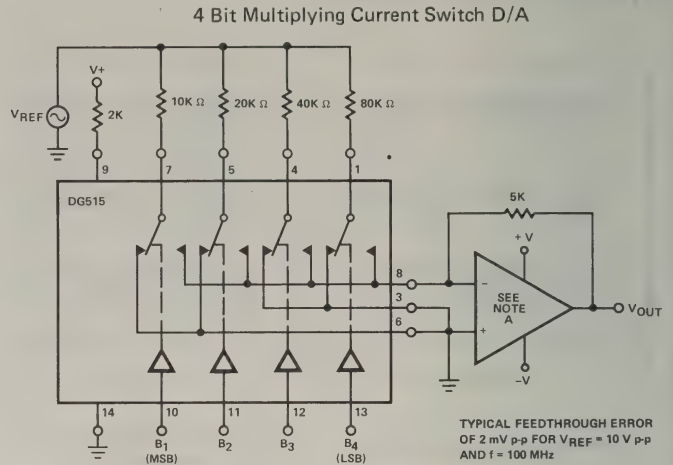
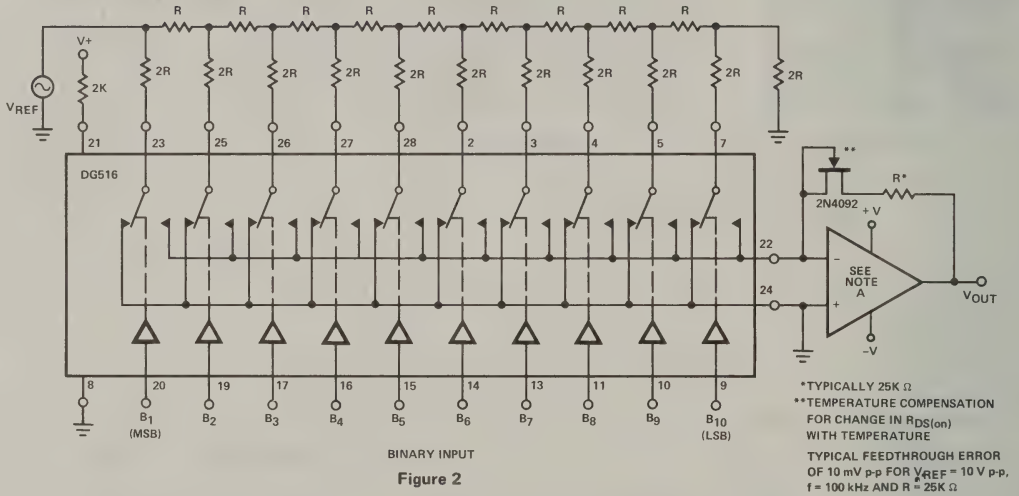


Figure 1

## 10 Bit D/A Converter



## Unipolar Binary Operation

DIGITAL INPUT	ANALOG OUTPUT
1 1 1 1 1 1 1 1 1 1	$-V_{REF} (1 - 2^{-10})$
1 0 0 0 0 0 0 0 0 1	$-V_{REF} (1/2 + 2^{-10})$
1 0 0 0 0 0 0 0 0 0	$-V_{REF}/2$
0 1 1 1 1 1 1 1 1 1	$-V_{REF} (1/2 - 2^{-10})$
0 0 0 0 0 0 0 0 0 1	$-V_{REF} (2^{-10})$
0 0 0 0 0 0 0 0 0 0	0

Figure 3

### NOTE:

Op-Amp characteristics effect D/A accuracy and settling time. The following Op-Amps, listed in order of increasing speed, are suggested:

1. LM101A

2. LF156A

3. LM118



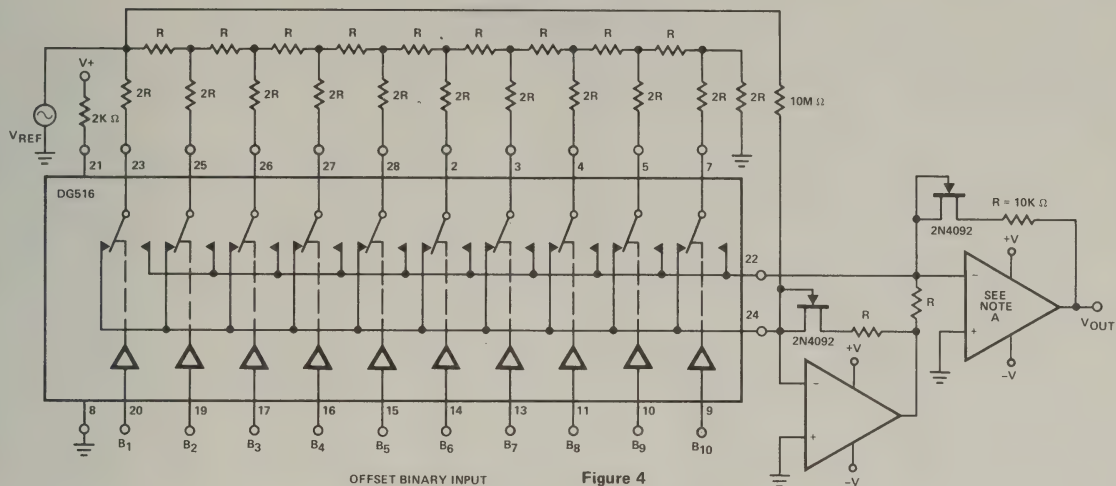
10 Bit, 4 Quadrant Multiplying DAC  
(Offset Binary Coding)

Figure 4

## Bipolar (Offset Binary)\* Operation

DIGITAL INPUT	ANALOG OUTPUT
1 1 1 1 1 1 1 1 1 1	$-V_{REF} (1 - 2^{-9})$
1 0 0 0 0 0 0 0 0 1	$-V_{REF} (2^{-9})$
1 0 0 0 0 0 0 0 0 0	0
0 1 1 1 1 1 1 1 1 1	$V_{REF} (2^{-9})$
0 0 0 0 0 0 0 0 0 1	$V_{REF} (1 - 2^{-9})$
0 0 0 0 0 0 0 0 0 0	$V_{REF}$

NOTE: 1 LSB =  $2^{-9} V_{REF}$

\*Complementing B<sub>1</sub> (MSB) will give 2's complement coding.

Figure 5

## Unipolar Binary Operation

DIGITAL INPUT	ANALOG OUTPUT
1 1 1 1 1 1 1 1 1 1 1 1	$-V_{REF} (1 - 2^{-14})$
1 0 0 0 0 0 0 0 0 0 0 0 1	$-V_{REF} (1/2 + 2^{-14})$
1 0 0 0 0 0 0 0 0 0 0 0 0	$-V_{REF}/2$
0 1 1 1 1 1 1 1 1 1 1 1	$-V_{REF} (1/2 - 2^{-14})$
0 0 0 0 0 0 0 0 0 0 0 0 1	$-V_{REF} (2^{-14})$
0 0 0 0 0 0 0 0 0 0 0 0 0	0

Figure 6

## 14 Bit Binary DAC (unipolar)

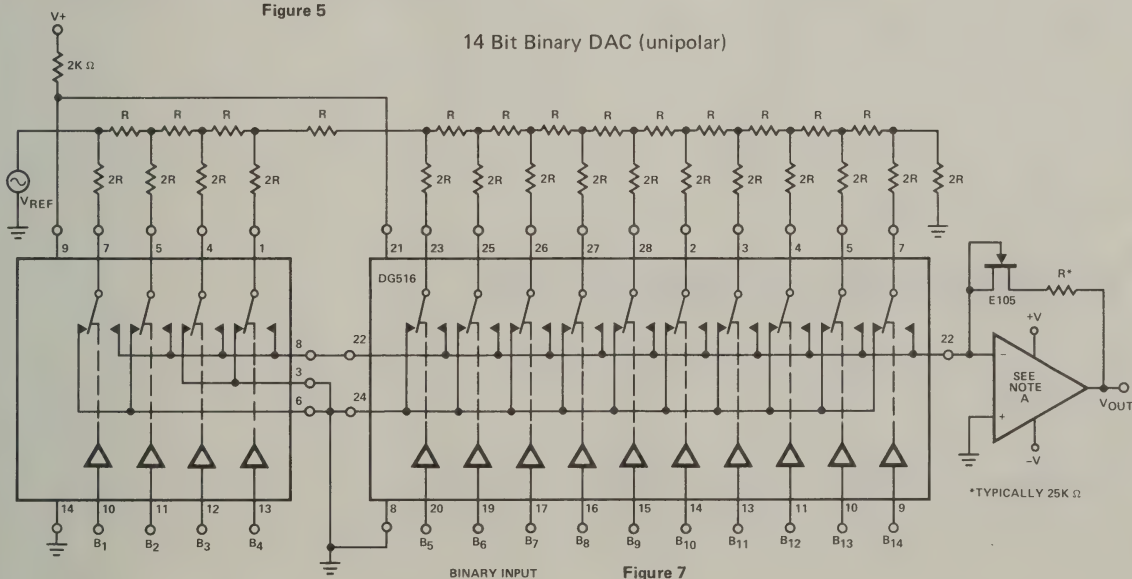


Figure 7

## NOTE:

A. Op-Amp characteristics effect D/A accuracy and settling time. The following Op-Amps, listed in order of increasing speed, are suggested:

1. LM101A
2. LF156A
3. LM118





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# Die Process Information

Siliconix is a large-volume supplier of die to the hybrid industry. Both military and industrial grades are available. Screening includes 100% DC electrical probe and 100% visual inspection of each die.

## PHYSICAL DATA

Physical layout and dimensions are presented in the Die Topography section. Die are supplied to length and width dimensions which have an accuracy of  $\pm 0.003$  inches. Thickness will be 0.015 inches ( $\pm 0.001$ ) for integrated circuit die and 0.008 inches ( $\pm 0.002$ ) for FETs.

Bonding pad location may be identified from the die topography shown. Contact factory for ordering information.

Each die or wafer is passivated with approximately 8,000 angstroms of non-crystalline glass.

FET chips are supplied with gold backing; gold backing is available as an option for integrated circuits.

Die metallization is deposited aluminum approximately 12,000 angstroms thick.

## DIE SCREENING CRITERIA

**Electrical Probe** — All dice are 100% probed in wafer form at 25°C to DC criteria designed to support "A" suffix DC parameters. An optional screen to "C" suffix limits is available.

**Visual Criteria** — All die receives a visual inspection to MIL-STD-883, Method 2010, Condition B criteria. Siliconix QC Department samples each lot to an LTPD of 10%. Alternate visual criteria, including Method 2010, Condition A, or Siliconix Industrial criteria are available as options.

## PACKAGING

Die are supplied in dust-proof, anti-static waffle packs (see illustration).

## ASSEMBLY

The customer's interests will best be served if static sensitivity handling procedures are used.

## PART NUMBER DESIGNATIONS

See ordering information.

## Options

(Price will be quoted upon request.)

*SEM* — Scanning electron microscope examination and control in accordance with MIL-STD-883 Method 2018 can be ordered on die and wafers. SEM, wafer qualification should be specified as a separate line item on a request for quote.

## Wafer Qualification to Unprobed Parameters

*Wafer Qualification to Unprobed Parameters* — Sample testing of purchased die to demonstrate capability to perform at data sheet temperature extremes or to switching time test limits by use of LTPD techniques can be provided at additional cost.

*Alternate Electrical Probe* — A 100% DC electrical probe to support "C" Suffix 25°C electrical specs is available for monolithic parts only. ("IDICE" ordering information.)

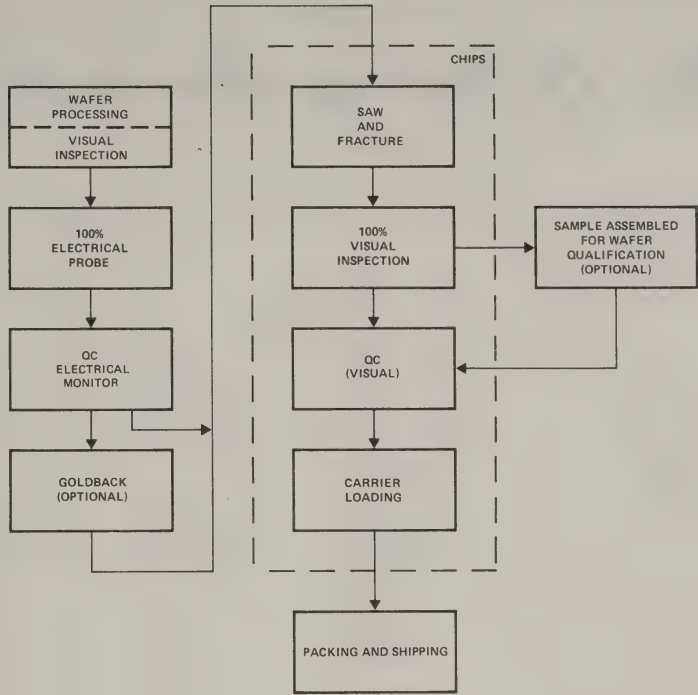
Visual inspection to customer generated specifications can be provided.

*Alternate Electrical Probe* — A 100% DC electrical probe to support "C" Suffix 25° electrical specs is available for monolithic parts only ("DICE" ordering information.)

*Gold Backing* — Die may be purchased with gold alloyed to the backside. This is a special order item. Gold thickness would be as follows:

- FETs (NC, NH, NIP) 750Å min
- IC's (all) 3500Å min

*Hot Probe* — Siliconix has chip processing distributors with hot probe capability available.



Chip Packaging

Chips are packaged as individual die in the flat waffle carrier illustrated in Figure 1. The carrier has a cavity size adequate to allow ease of loading/unloading and also prevents die from rotating within the cavity.

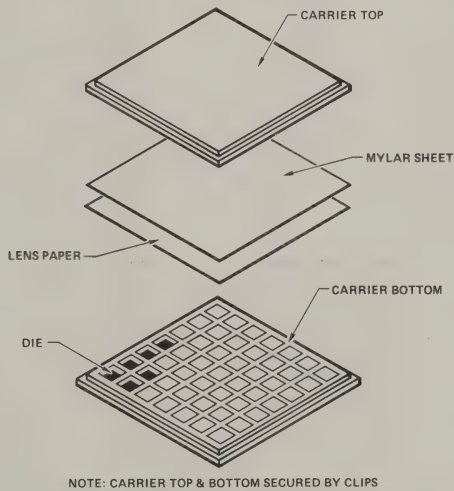
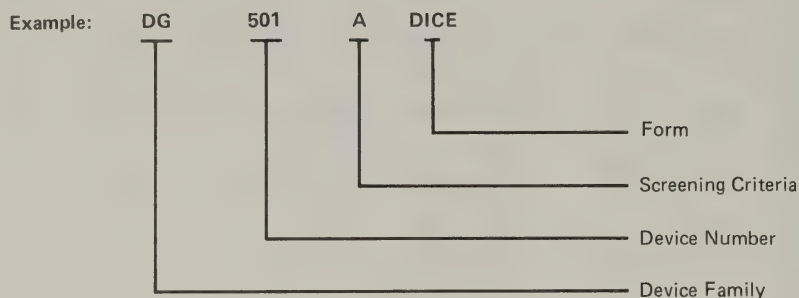


Figure 1

# Die Ordering Information

## 1. Monolithic Chips:



### DEVICE FAMILY

(1, 2 or 3 Letters)

- D — Drivers for FET Switches
- DG — Analog Switches
- DGM — Analog Switches
- G — Multi-Channel FETs
- Si — Siliconix Second Source Part

### DEVICE NUMBER

(3 or 4 Digit Numbers)

### SCREENING CRITERIA

(1 Letter)

- A — Electrically probed @ 25°C to "A" Suffix of respective data sheet; visual criteria screening to MIL-STD-883, Method 2010 Condition B.
- I — Electrically probed @ 25°C to "C" Suffix of respective data sheet; visual criteria screening to Siliconix Specification 5018.

### FORM

(4 Letters)

- DICE — Chips waffle packed per Figure 4 in Die Process Information



## 2. Multichip

To order die which form multichip devices the driver chip and corresponding JFETs should be ordered using the geometry designations as shown in Table 1 below.

Example:

For D9190 die, order  
CMJB1000  
and NC1000

To determine number of JFETs required to go with each driver in a multichip device, see number in parenthesis following geometry codes as shown in table below.

Table 1

Siliconix Part No.	Geometry Code		Technology
	Driver	FET	
DG123	IBAF/MABA	See D123 and G115	PMOS Switch
DG125	IBAF/MABA	See D125 and G115	PMOS Switch
DG126	LODC1000	NC2000(4)	JFET Switch
DG129	LODC1000	NC1000(4)	JFET Switch
DG133	LODC1000	NC1000(2)	JFET Switch
DG134	LODC1000	NC2000(2)	JFET Switch
DG139	LODF1000	NC1000(4)	JFET Switch
DG140	LODC1000	NIP1000(4)	JFET Switch
DG141	LODC1000	NIP1000(2)	JFET Switch
DG142	LODF1000	NC2000(4)	JFET Switch
DG143	LODF1000	NC2000(2)	JFET Switch
DG144	LODF1000	NC1000(2)	JFET Switch
DG145	LODF1000	NIP1000(4)	JFET Switch
DG146	LODF1000	NIP1000(2)	JFET Switch
DG151	LODC1000	NIP1000(2)	JFET Switch
DG152	LODC1000	NC1000(2)	JFET Switch
DG153	LODC1000	NIP1000(4)	JFET Switch
DG154	LODC1000	NC1000(4)	JFET Switch
DG161	LODF1000	NIP1000(2)	JFET Switch
DG162	LODF1000	NC1000(2)	JFET Switch
DG163	LODF1000	NIP1000(4)	JFET Switch
DG164	LODF1000	NC1000(4)	JFET Switch
DG180	CMJB1000	NIP1000(2)	JFET Switch
DG181	CMJB1000	NC1000(2)	JFET Switch
DG182	CMJB1000	NC2000(2)	JFET Switch
DG183	CMJA1000	NIP1000(4)	JFET Switch
DG184	CMJA1000	NC1000(4)	JFET Switch
DG185	CMJA1000	NC2000(4)	JFET Switch
DG186	CMJC1000	NIP1000(2)	JFET Switch
DG187	CMJC1000	NC1000(2)	JFET Switch
DG188	CMJC1000	NC2000(2)	JFET Switch
DG189	CMJB1000	NIP1000(4)	JFET Switch
DG190	CMJB1000	NC1000(4)	JFET Switch
DG191	CMJB1000	NC2000(4)	JFET Switch
DG281	CMJB1000	NH1000(2)	JFET Switch
DG284	CMJA1000	NH1000(4)	JFET Switch
DG287	CMJC1000	NH1000(2)	JFET Switch
DG290	CMJB1000	NH1000(4)	JFET Switch

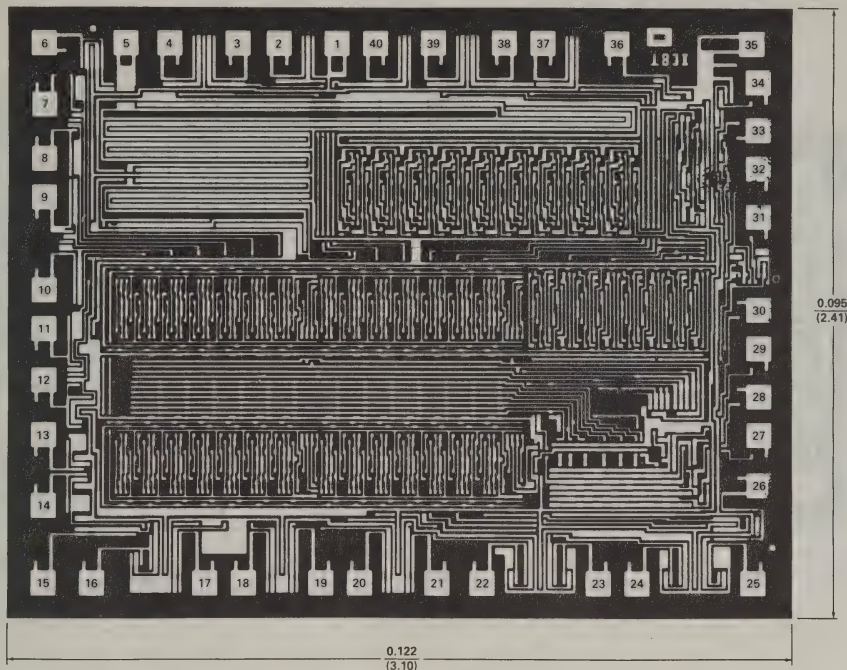
## 3. Options

The following options are considered "special" and a special part number will be assigned:

1. Die in wafer form
2. Goldbacking on Integrated Circuit die
3. Class A visual
4. Customer visual criteria

Please identify as "similar to \_\_\_\_\_ with following additional conditions \_\_\_\_\_."

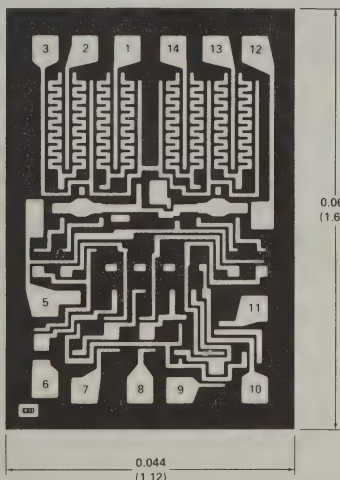
# **Die Topography Information Monolithic**



PAD NO.	FUNCTION	PAD NO.	FUNCTION	PAD NO.	FUNCTION
1	V <sub>DD</sub>	15	c <sub>3</sub>	29	B <sub>2</sub>
2	e <sub>1</sub>	16	d <sub>3</sub>	30	B <sub>3</sub>
3	g <sub>1</sub>	17	e <sub>3</sub>	31	D <sub>1</sub>
4	f <sub>1</sub>	18	g <sub>3</sub>	32	D <sub>2</sub>
5	BP	19	f <sub>3</sub>	33	D <sub>3</sub>
6	a <sub>2</sub>	20	a <sub>4</sub>	34	D <sub>4</sub>
7	b <sub>2</sub>	21	b <sub>4</sub>	35	V <sub>SS</sub>
8	c <sub>2</sub>	22	c <sub>4</sub>	36	OSC
9	d <sub>2</sub>	23	d <sub>4</sub>	37	a <sub>1</sub>
10	e <sub>2</sub>	24	e <sub>4</sub>	38	b <sub>1</sub>
11	g <sub>2</sub>	25	g <sub>4</sub>	39	c <sub>1</sub>
12	f <sub>2</sub>	26	f <sub>4</sub>	40	d <sub>1</sub>
13	a <sub>3</sub>	27	B <sub>0</sub>		
14	b <sub>3</sub>	28	B <sub>1</sub>		

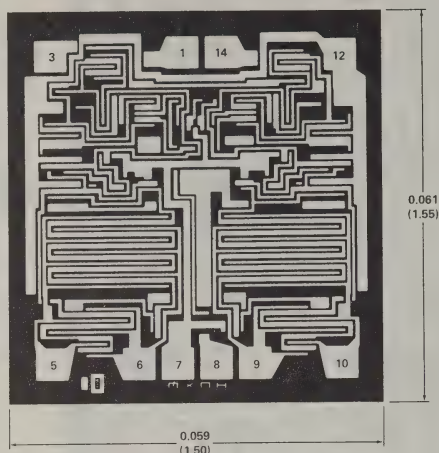
Substrate = V<sub>DD</sub>ALL DIMENSIONS IN INCHES  
(ALL DIMENSIONS IN MILLIMETERS)

DF412

Pin numbers are for  
dual in-line packages

PIN NO.	FUNCTION
1	SOURCE 3
2	SOURCE 4
3	DRAIN
5	V- (SUBSTRATE)
6	INPUT 4
7	INPUT 3
8	INPUT 2
9	INPUT 1
10	V <sub>L</sub>
11	V <sub>R</sub>
12	V <sub>+</sub>
13	SOURCE 1
14	SOURCE 2

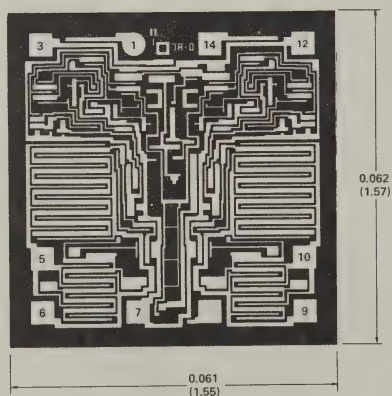
DG172



DG200

PIN NO.	FUNCTION
1	INPUT 2
3	GROUND
5	SOURCE 2
6	DRAIN 2
7	V-
8	V <sub>REF</sub>
9	DRAIN 1
10	SOURCE 1
12	V+ (SUBSTRATE)
14	INPUT 1

Pin numbers are for dual in line packages.



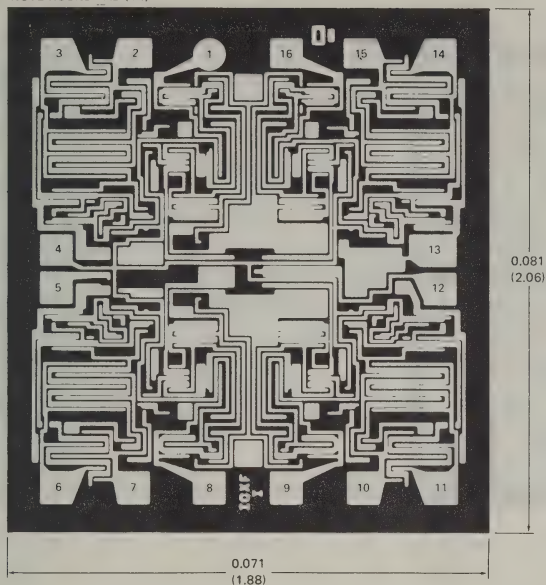
DG200A

PIN NO.	FUNCTION
1	INPUT 2
3	GROUND
5	SOURCE 2
6	DRAIN 2
7	V-
9	DRAIN 1
10	SOURCE 1
12	V+ (SUBSTRATE)
14	INPUT 1

Pin numbers are for dual in line packages.



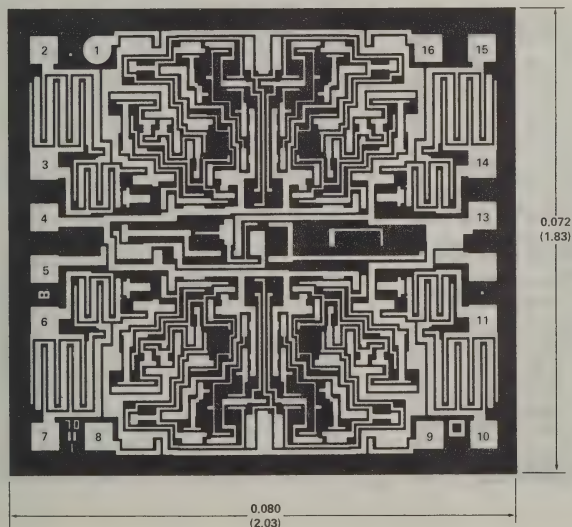
NOTE ROUND PAD (#1)



PIN NO.	FUNCTION
1	INPUT 1
2	DRAIN 1
3	SOURCE 1
4	V-
5	GND
6	SOURCE 4
7	DRAIN 4
8	INPUT 4
9	INPUT 3
10	DRAIN 3
11	SOURCE 3
12	VREF
13	V+ (SUBSTRATE)
14	SOURCE 2
15	DRAIN 2
16	INPUT 2

Pin numbers are for dual in line packages

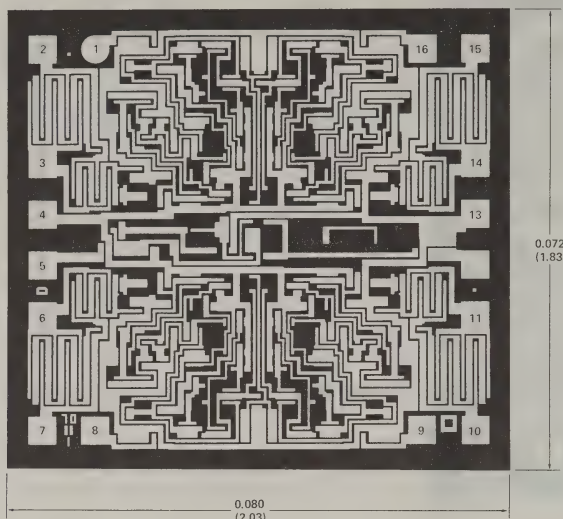
DG201



PIN NO.	FUNCTION
1	INPUT 1
2	DRAIN 1
3	SOURCE 1
4	V-
5	GND
6	SOURCE 4
7	DRAIN 4
8	INPUT 4
9	INPUT 3
10	DRAIN 3
11	SOURCE 3
13	V+ (SUBSTRATE)
14	SOURCE 2
15	DRAIN 2
16	INPUT 2

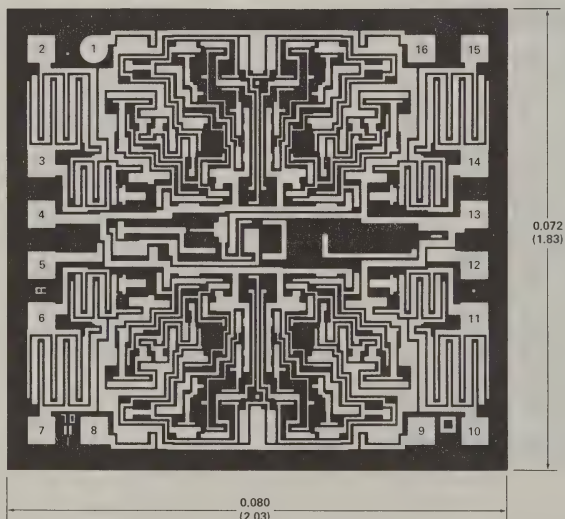
Pin numbers are for dual in-line packages

DG201A



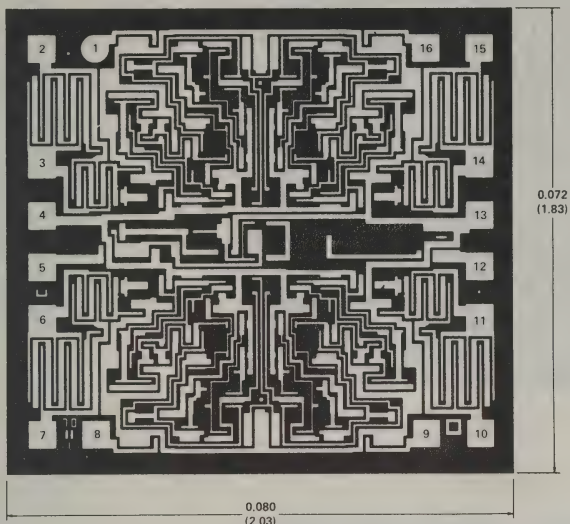
PIN NO.	FUNCTION
1	INPUT 1
2	DRAIN 1
3	SOURCE 1
4	V <sub>-</sub>
5	GROUND
6	SOURCE 4
7	DRAIN 4
8	INPUT 4
9	INPUT 3
10	DRAIN 3
11	SOURCE 3
13	V <sub>+</sub> (SUBSTRATE)
14	SOURCE 2
15	DRAIN 2
16	INPUT 2

DG202



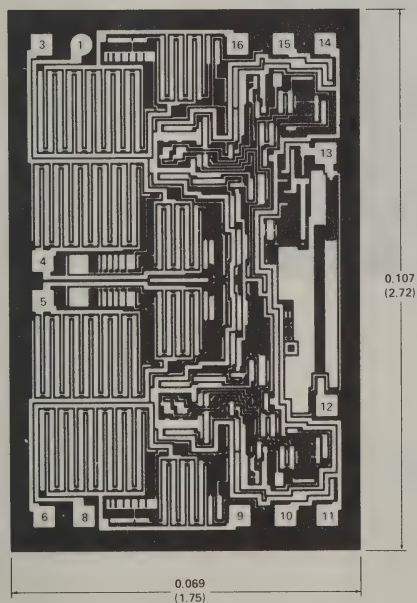
PIN NO.	FUNCTION
1	INPUT 1
2	DRAIN 1
3	SOURCE 1
4	V <sub>-</sub>
5	GROUND
6	SOURCE 4
7	DRAIN 4
8	INPUT 4
9	INPUT 3
10	DRAIN 3
11	SOURCE 3
12	V <sub>L</sub>
13	V <sub>+</sub> (SUBSTRATE)
14	SOURCE 2
15	DRAIN 2
16	INPUT 2

DG211



PIN NO.	FUNCTION
1	INPUT 1
2	DRAIN 1
3	SOURCE 1
4	V <sub>-</sub>
5	GROUND
6	SOURCE 4
7	DRAIN 4
8	INPUT 4
9	INPUT 3
10	DRAIN 3
11	SOURCE 3
12	V <sub>L</sub>
13	V <sub>+</sub> (SUBSTRATE)
14	SOURCE 2
15	DRAIN 2
16	INPUT 2

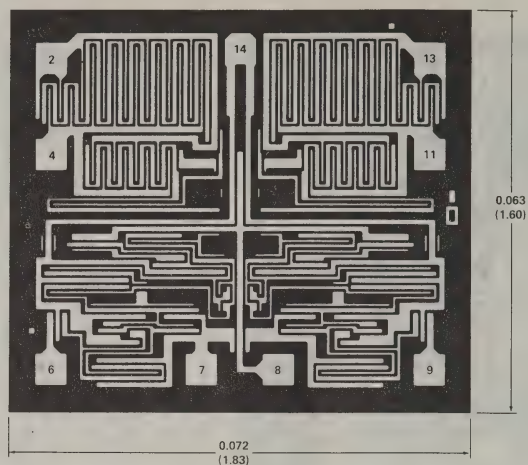
DG212



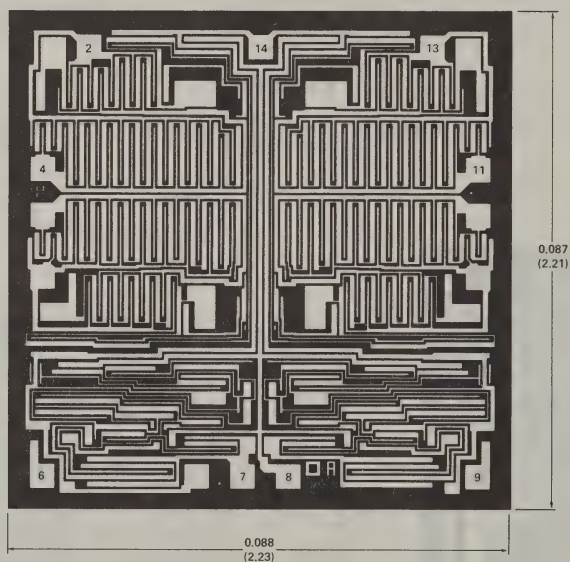
PIN NO.	FUNCTION
1	DRAIN 1
3	DRAIN 3
4	SOURCE 3
5	SOURCE 4
6	DRAIN 4
8	DRAIN 2
9	SOURCE 2
10	INPUT 2
11	V <sub>+</sub> (SUBSTRATE)
12	V <sub>L</sub>
13	GND
14	V <sub>-</sub>
15	INPUT 1
16	SOURCE 1

Pin numbers are for  
dual-in-line packages

DG243



DG300

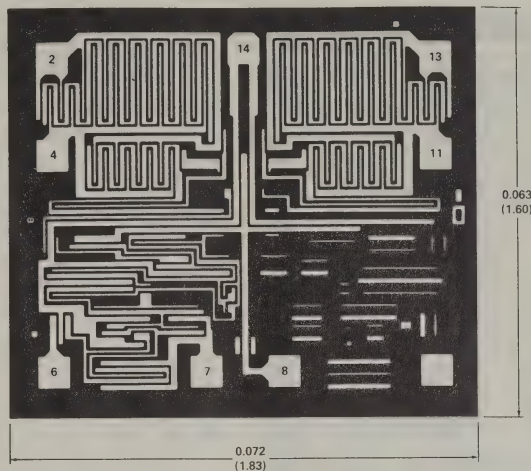


DG300A

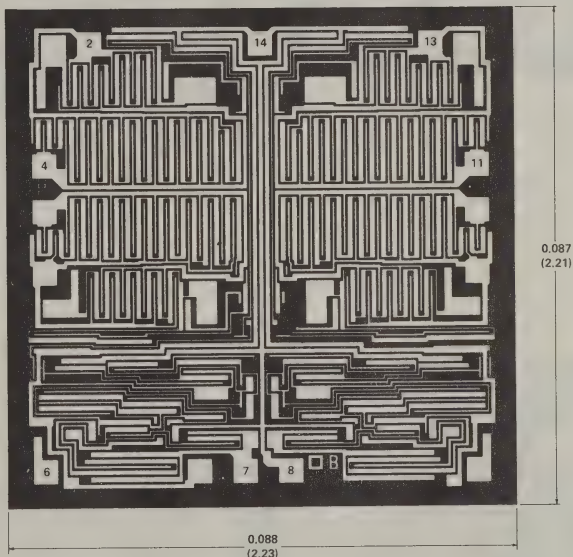
PIN NO.	FUNCTION
2	DRAIN 1
4	SOURCE 1
6	INPUT 1
7	GROUND
8	V-
9	INPUT 2
11	SOURCE 2
13	DRAIN 2
14	V+ (SUBSTRATE)

Pin numbers are for dual in-line packages





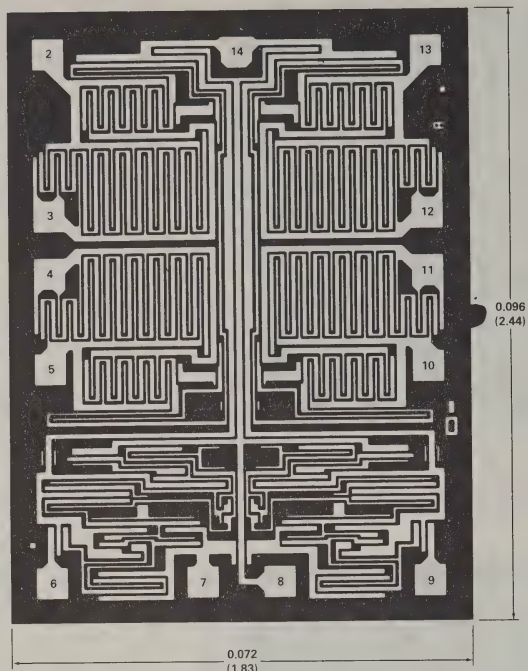
DG301



DG301A

PIN NO.	FUNCTION
2	DRAIN 1
4	SOURCE 1
6	INPUT 1
7	GROUND
8	V-
11	SOURCE 2
13	DRAIN 2
14	V+ (SUBSTRATE)

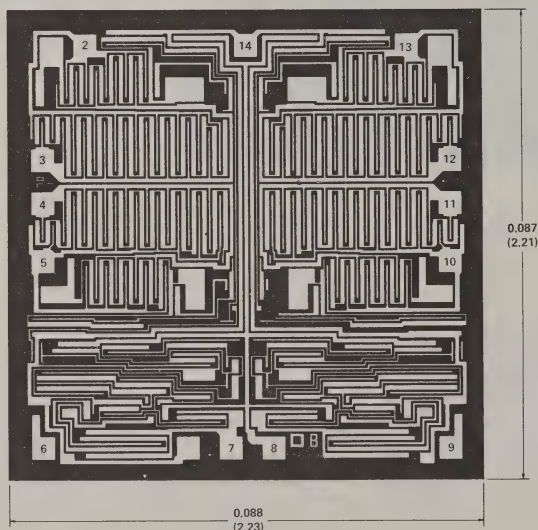
Pin numbers are for dual in-line packages



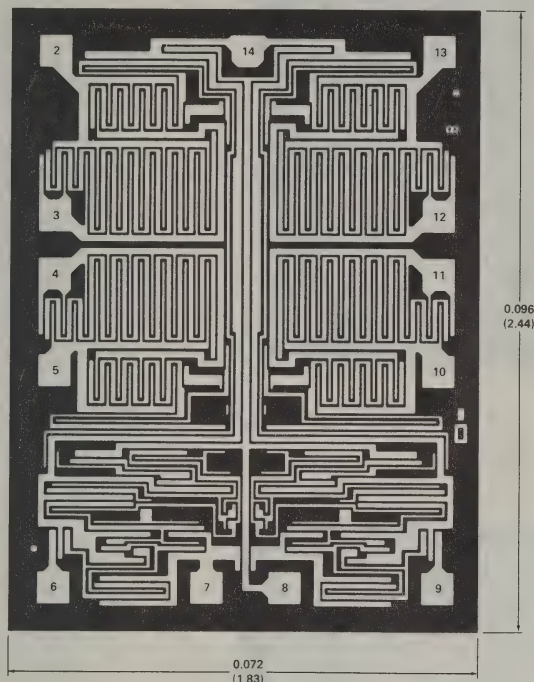
DG302

PIN NO.	FUNCTION
2	SOURCE 3
3	DRAIN 3
4	DRAIN 1
5	SOURCE 1
6	INPUT 1
7	GROUND
8	V <sub>-</sub>
9	INPUT 2
10	SOURCE 2
11	DRAIN 2
12	DRAIN 4
13	SOURCE 4
14	V <sub>+</sub> (SUBSTRATE)

Pin numbers are for dual in-line packages



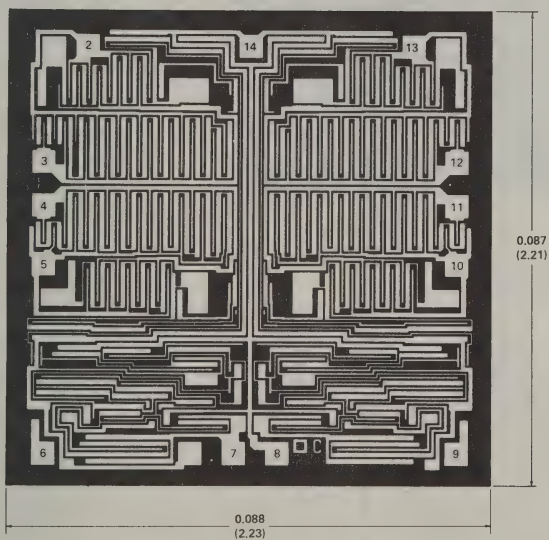
DG302A



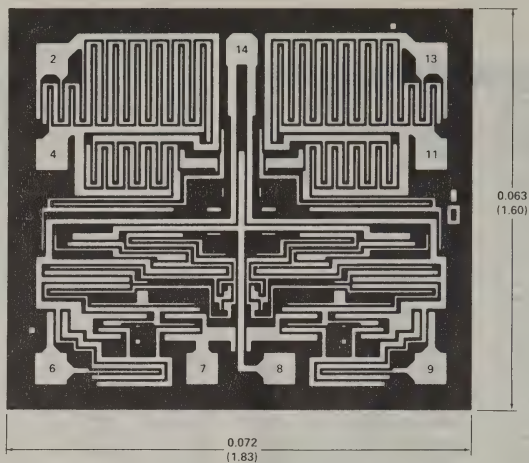
DG303

PIN NO.	FUNCTION
2	SOURCE 3
3	DRAIN 3
4	DRAIN 1
5	SOURCE 1
6	INPUT 1
7	GROUND
8	V-
9	INPUT 2
10	SOURCE 2
11	DRAIN 2
12	DRAIN 4
13	SOURCE 4
14	V+ (SUBSTRATE)

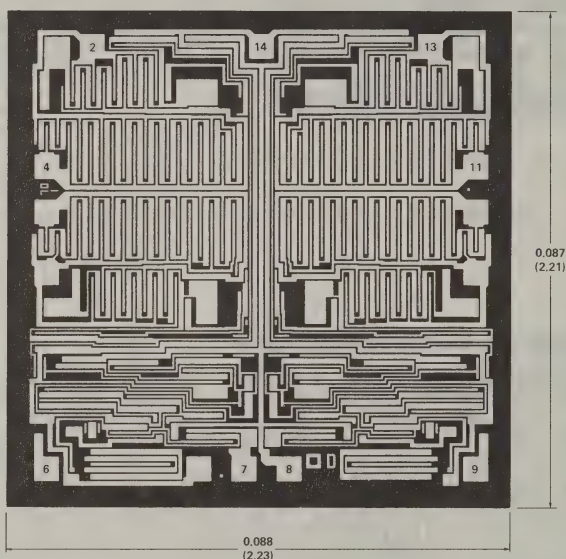
Pin numbers are for dual in-line packages



DG303A



**DG304**

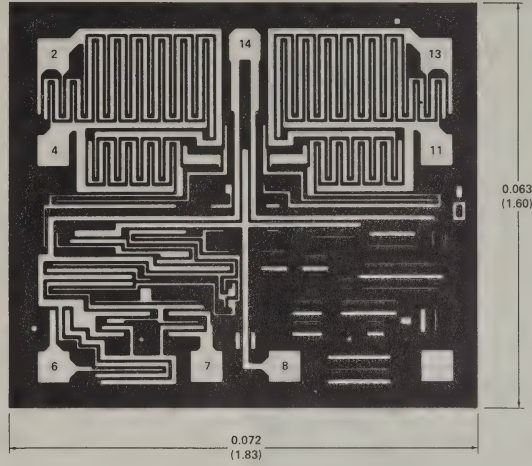


**DG304A**

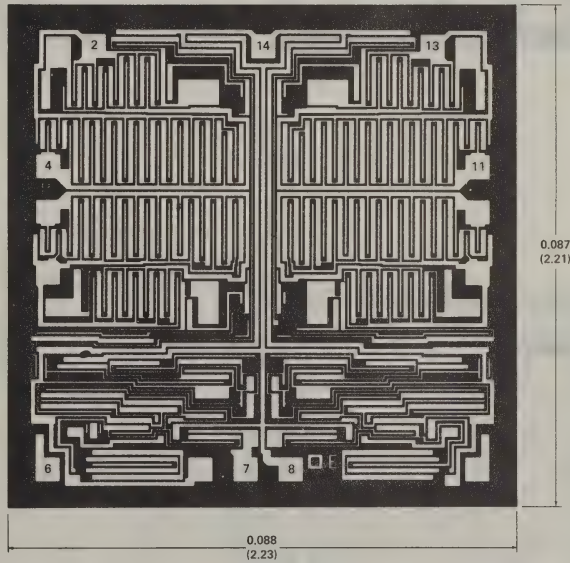
PIN NO.	FUNCTION
2	DRAIN 1
4	SOURCE 1
6	INPUT 1
7	GROUND
8	V-
9	INPUT 2
11	SOURCE 2
13	DRAIN 2
14	V+ (SUBSTRATE)

Pin numbers are for dual in-line packages





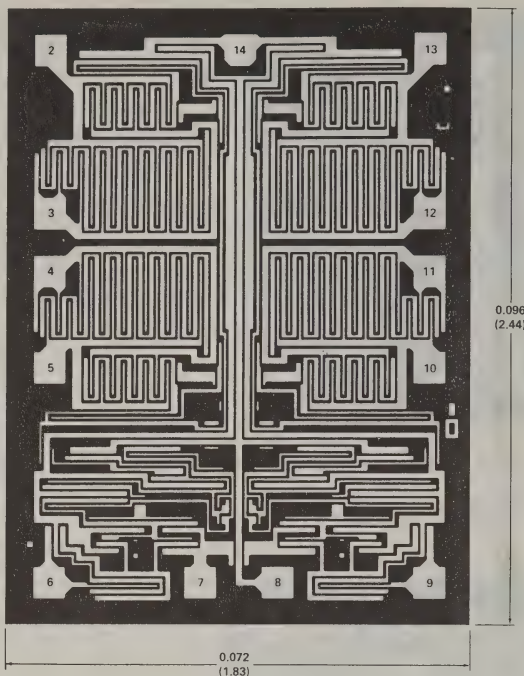
DG305



DG305A

PIN NO.	FUNCTION
2	DRAIN 1
4	SOURCE 1
6	INPUT 1
7	GROUND
8	V-
11	SOURCE 2
13	DRAIN 2
14	V+ (SUBSTRATE)

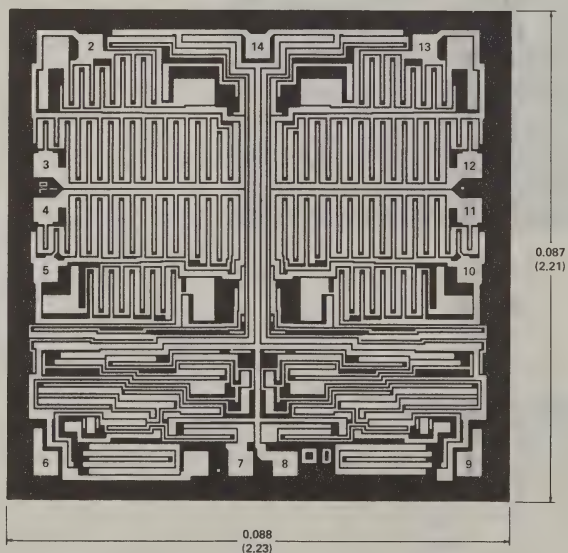
Pin numbers for dual in-line packages



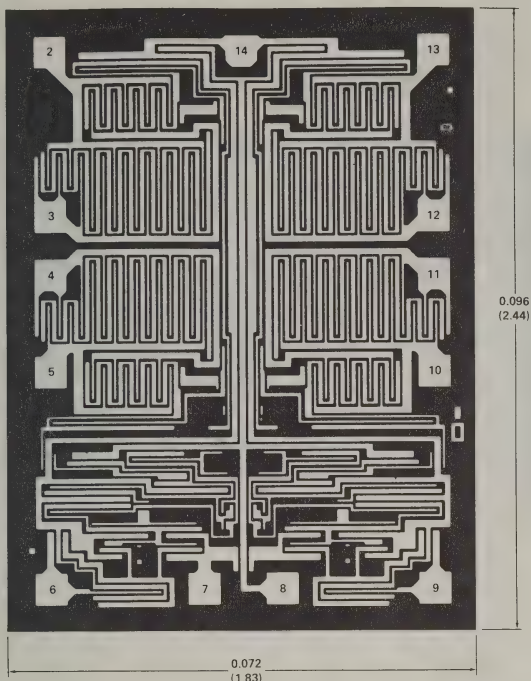
DG306

PIN NO.	FUNCTION
2	SOURCE 3
3	DRAIN 3
4	DRAIN 1
5	SOURCE 1
6	INPUT 1
7	GROUND
8	V-
9	INPUT 2
10	SOURCE 2
11	DRAIN 2
12	DRAIN 4
13	SOURCE 4
14	V+ (SUBSTRATE)

Pin numbers are for dual in-line packages



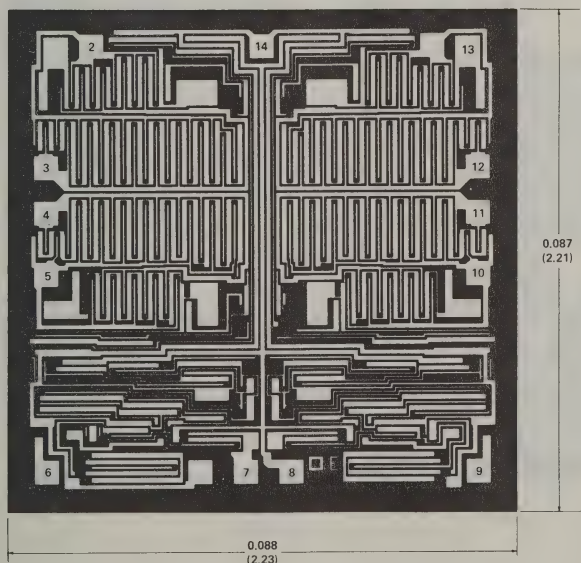
DG306A



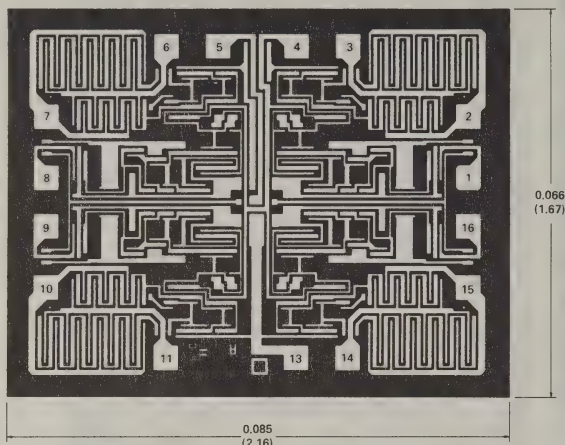
DG307

PIN NO.	FUNCTION
2	SOURCE 3
3	DRAIN 3
4	DRAIN 1
5	SOURCE 1
6	INPUT 1
7	GROUND
8	V-
9	INPUT 2
10	SOURCE 2
11	DRAIN 2
12	DRAIN 4
13	SOURCE 4
14	V+ (SUBSTRATE)

Pin numbers are for dual in-line packages



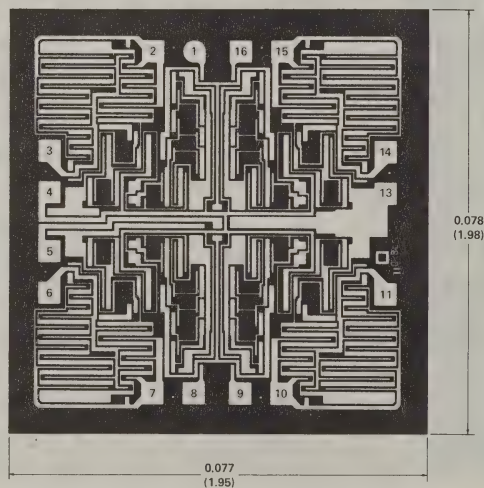
DG307A



PIN NO.	FUNCTION
1	INPUT 1
2	DRAIN 1
3	SOURCE 1
4	V-
5	GROUND
6	SOURCE 4
7	DRAIN 4
8	INPUT 4
9	INPUT 3
10	DRAIN 3
11	DRAIN 3
13	V+ (SUBSTRATE)
14	SOURCE 2
15	DRAIN 2
16	INPUT 2

Pin numbers are for dual in-line packages

DG308

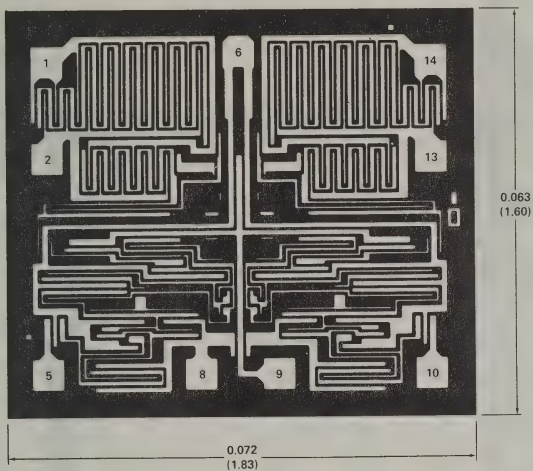


PIN NO.	FUNCTION
1	INPUT 1
2	DRAIN 1
3	SOURCE 1
4	V-
5	GROUND
6	SOURCE 4
7	DRAIN 4
8	INPUT 4
9	INPUT 3
10	DRAIN 3
11	DRAIN 3
13	V+ (SUBSTRATE)
14	SOURCE 2
15	DRAIN 2
16	INPUT 2

Pin numbers are for dual in-line packages

DG309

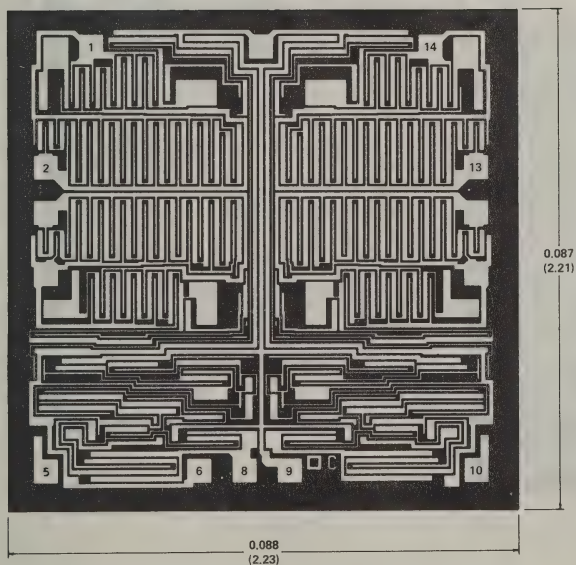




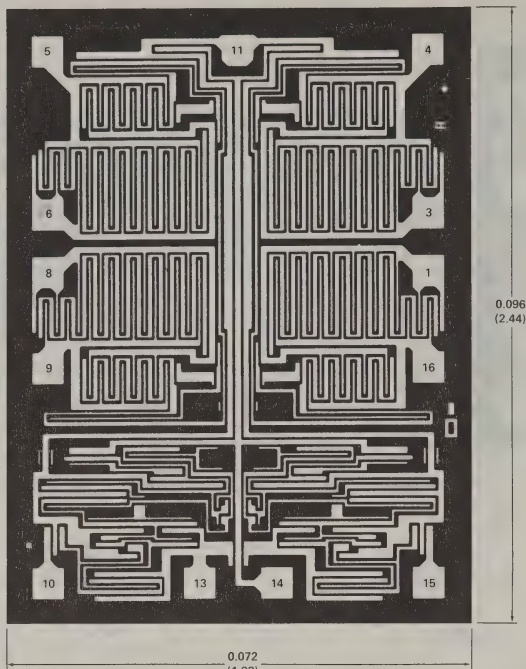
DG381

PIN NO.	FUNCTION
1	SOURCE 1
2	DRAIN 1
5	INPUT 1
6	V+ (SUBSTRATE)
8	V <sub>R</sub>
9	V <sub>-</sub>
10	INPUT 2
13	DRAIN 2
14	SOURCE 2

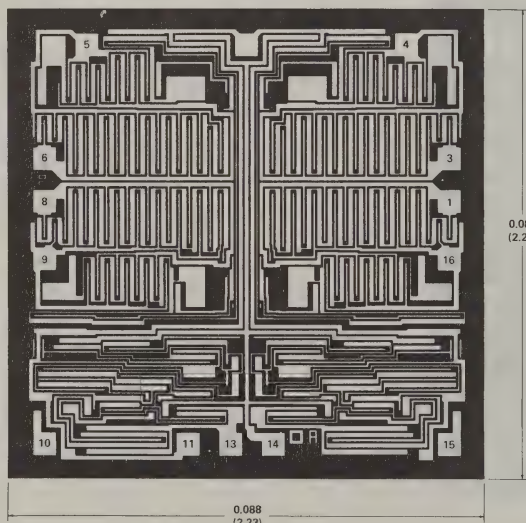
Pin numbers are for dual in-line packages



DG381A



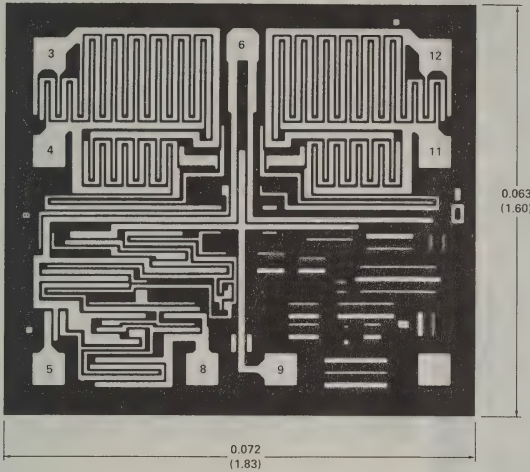
DG384



DG384A

PIN NO.	FUNCTION
1	DRAIN 1
3	DRAIN 3
4	SOURCE 3
5	SOURCE 4
6	DRAIN 4
8	DRAIN 2
9	SOURCE 2
10	INPUT 2
11	V+ (SUBSTRATE)
13	GROUND
14	V-
15	INPUT 1
16	SOURCE 1

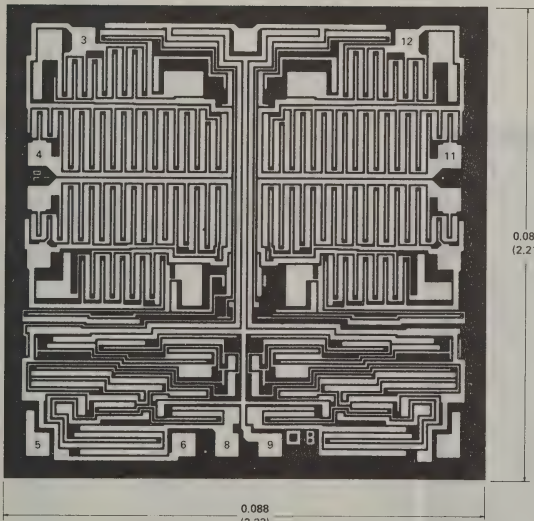
Pin numbers are for dual in-line packages



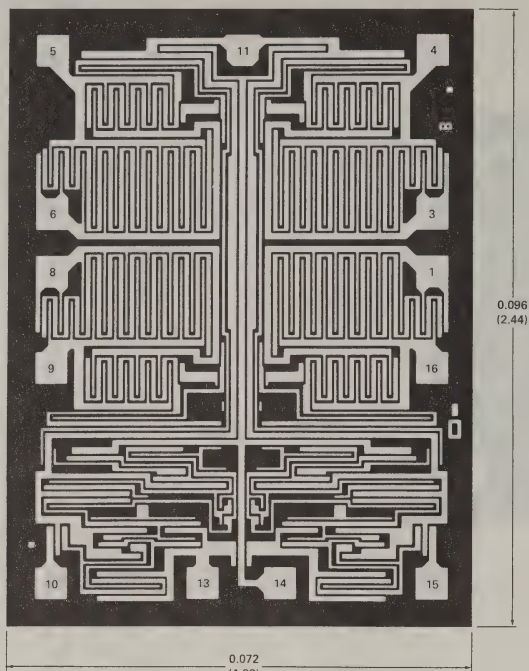
DG387

PIN NO.	FUNCTION
3	DRAIN 1
4	SOURCE 1
5	INPUT 1
6	V+ (SUBSTRATE)
8	V <sub>R</sub>
9	V <sub>-</sub>
11	SOURCE 2
12	DRAIN 2

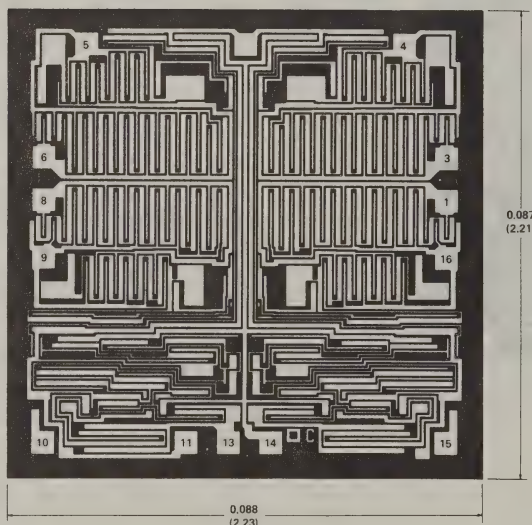
Pin numbers are for dual in-line packages



DG387A



DG390



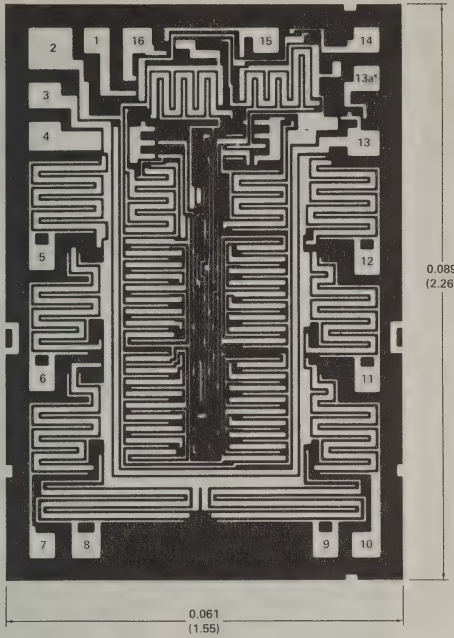
DG390A

PIN NO.	FUNCTION
1	INPUT 1
3	DRAIN 3
4	SOURCE 3
5	SOURCE 4
6	DRAIN 4
8	DRAIN 2
9	SOURCE 2
10	INPUT 2
11	V+ (SUBSTRATE)
13	GND
14	V-
15	INPUT 1
16	SOURCE 1

Pin numbers are for dual in-line packages



NOTE LARGE PAD (#2)



PIN NO.	FUNCTION
1	ENABLE
2†	V+ (SUBSTRATE)
3	DRAIN
4†	V+ (SUBSTRATE)
5	SOURCE 8
6	SOURCE 7
7	SOURCE 6
8	SOURCE 5
9	SOURCE 4
10	SOURCE 3
11	SOURCE 2
12	SOURCE 1
13	V-
14	ADDRESS 0
15	ADDRESS 1
16	ADDRESS 2

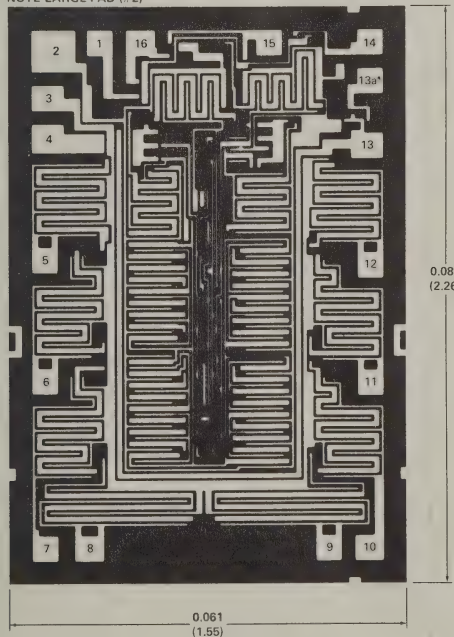
\*13a is connected to V-

† Pins 2 and 4 are interconnected, either one may be used

Pin numbers are for dual in-line packages

DG501

NOTE LARGE PAD (#2)

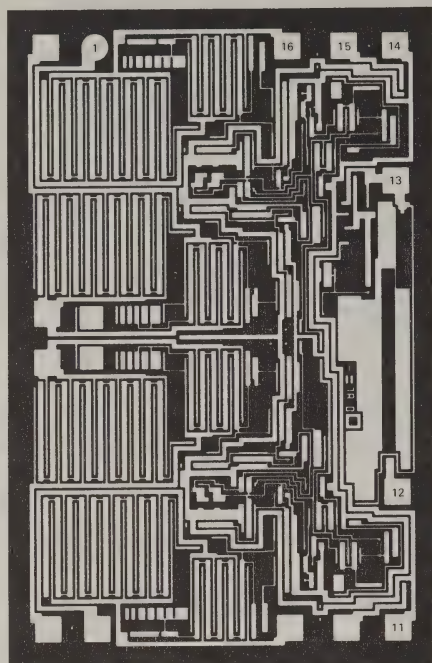


PIN NO.	FUNCTION
1	ENABLE
2*	V+ (SUBSTRATE)
3	DRAIN
4*	V+ (SUBSTRATE)
5	SOURCE 8
6	SOURCE 7
7	SOURCE 6
8	SOURCE 5
9	SOURCE 4
10	SOURCE 3
11	SOURCE 2
12	SOURCE 1
13	V-
14	ADDRESS 0
15	ADDRESS 1
16	ADDRESS 2

\*Pins 2 and 4 are interconnected, either one may be used

Pin numbers are for dual in-line packages

DG503

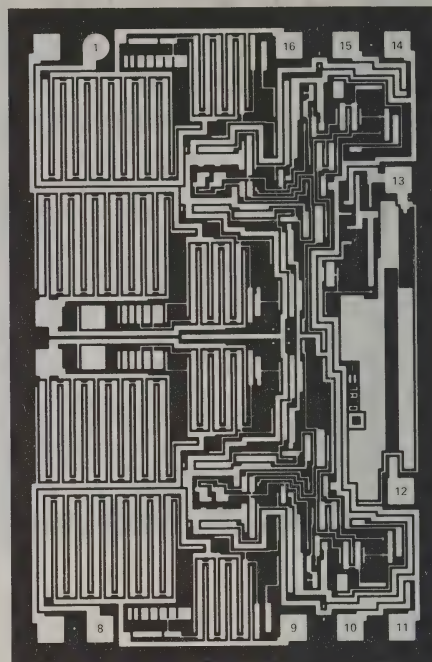


0.107  
(2.72)

0.069  
(1.75)

PIN NO.	FUNCTION
1	DRAIN 1
11	V+ (SUBSTRATE)
12	V <sub>L</sub>
13	GND
14	V-
15	INPUT 1
16	SOURCE 1

DG5040

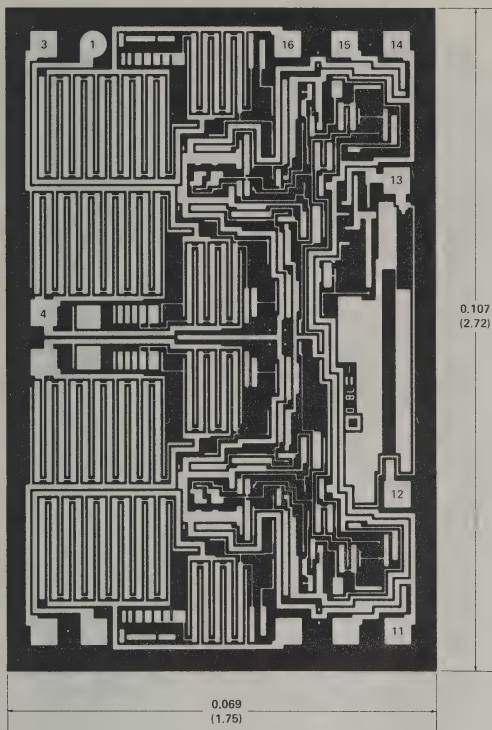


0.107  
(2.72)

0.069  
(1.75)

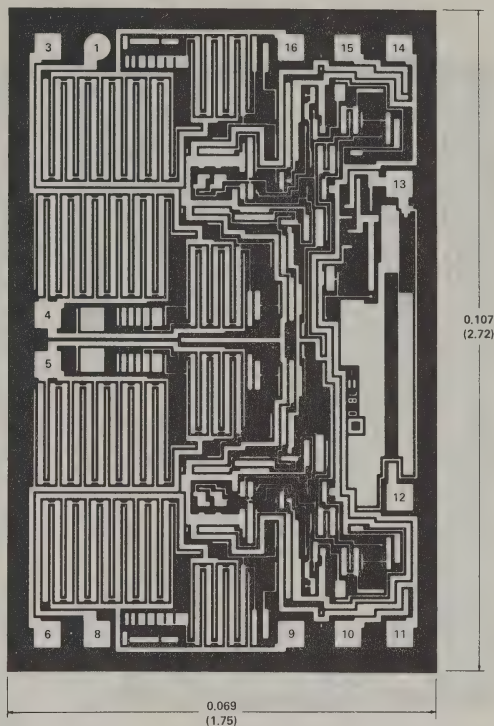
PIN NO.	FUNCTION
1	DRAIN 1
8	DRAIN 2
9	SOURCE 2
10	INPUT 2
11	V+ (SUBSTRATE)
12	V <sub>L</sub>
13	GND
14	V-
15	INPUT 1
16	SOURCE 1

DG5041



PIN NO.	FUNCTION
1	DRAIN 1
3	DRAIN 2
4	SOURCE 2
11	V+ (SUBSTRATE)
12	V <sub>L</sub>
13	GND
14	V-
15	INPUT 1
16	SOURCE 1

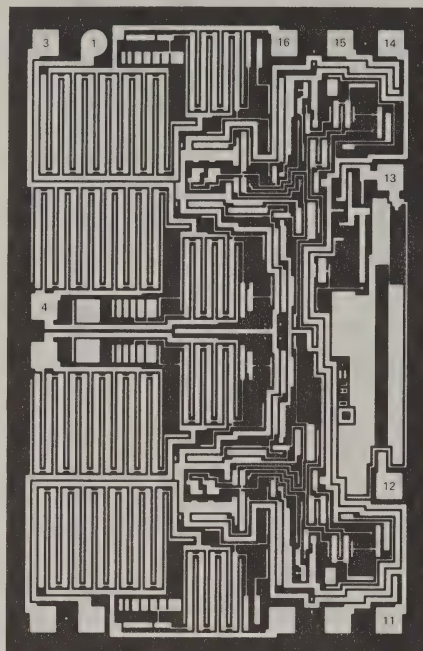
DG5042



PIN NO.	FUNCTION
1	DRAIN 1
3	DRAIN 3
4	SOURCE 3
5	SOURCE 4
6	DRAIN 4
8	DRAIN 2
9	SOURCE 2
10	INPUT 2
11	V+ (SUBSTRATE)
12	V <sub>L</sub>
13	GND
14	V-
15	INPUT 1
16	SOURCE 1

DG5043



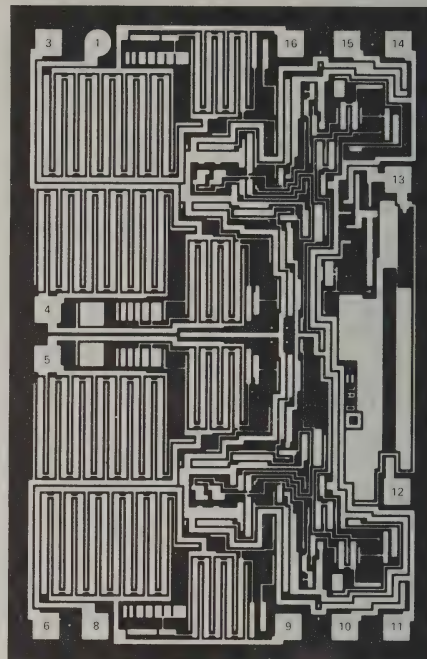


0.069  
(1.75)

0.107  
(2.72)

PIN NO.	FUNCTION
1	DRAIN 1
3	DRAIN 2
4	SOURCE 2
11	V+ (SUBSTRATE)
12	V <sub>L</sub>
13	GND
14	V-
15	INPUT 1
16	SOURCE 1

DG5044



0.069  
(1.75)

0.107  
(2.72)

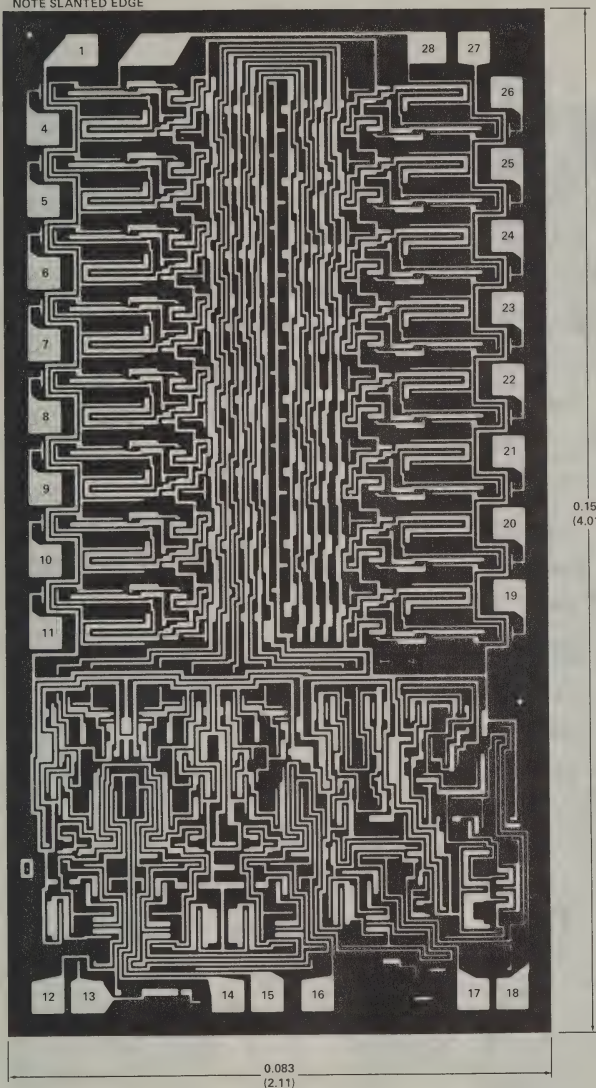
PIN NO.	FUNCTION
1	DRAIN 1
3	DRAIN 3
4	SOURCE 3
5	SOURCE 4
6	DRAIN 4
8	DRAIN 2
9	SOURCE 2
10	INPUT 2
11	V+ (SUBSTRATE)
12	V <sub>L</sub>
13	GND
14	V-
15	INPUT 1
16	SOURCE 1

Pin numbers are for dual-in-line packages.

DG5045

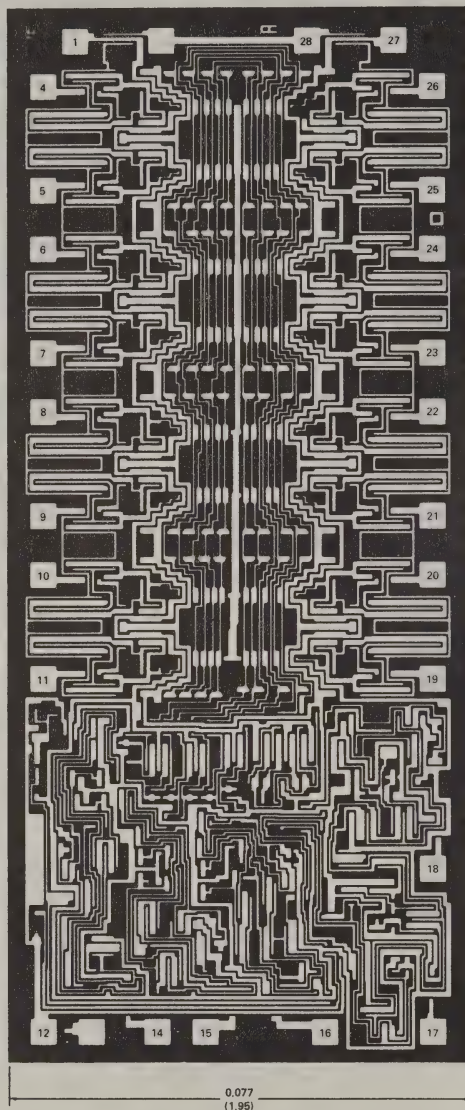


NOTE SLANTED EDGE



PIN NO.	FUNCTION
1	V+ (SUBSTRATE)
4	SOURCE 16
5	SOURCE 15
6	SOURCE 14
7	SOURCE 13
8	SOURCE 12
9	SOURCE 11
10	SOURCE 10
11	SOURCE 9
12	GROUND
13	VREF
14	ADDRESS 3
15	ADDRESS 2
16	ADDRESS 1
17	ADDRESS 0
18	ENABLE
19	SOURCE 1
20	SOURCE 2
21	SOURCE 3
22	SOURCE 4
23	SOURCE 5
24	SOURCE 6
25	SOURCE 7
26	SOURCE 8
27	V-
28	DRAIN

Pin numbers are for dual in-line packages

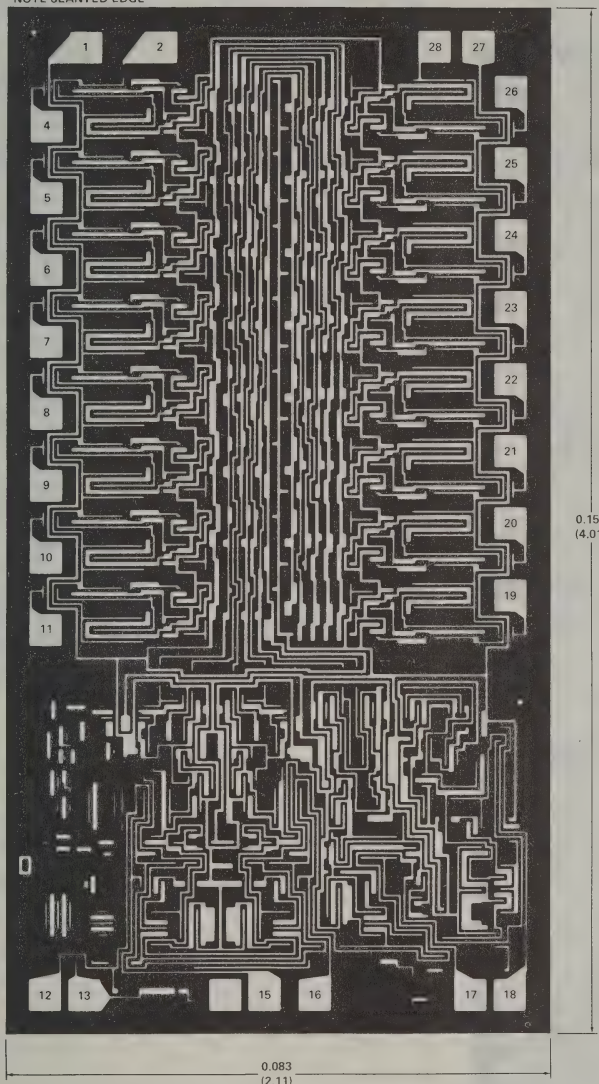


PIN NO.	FUNCTION
1	V+ (SUBSTRATE)
4	SOURCE 16
5	SOURCE 15
6	SOURCE 14
7	SOURCE 13
8	SOURCE 12
9	SOURCE 11
10	SOURCE 10
11	SOURCE 9
12	GROUND
14	ADDRESS 3
15	ADDRESS 2
16	ADDRESS 1
17	ADDRESS 0
18	ENABLE
19	SOURCE 1
20	SOURCE 2
21	SOURCE 3
22	SOURCE 4
23	SOURCE 5
24	SOURCE 6
25	SOURCE 7
26	SOURCE 8
27	V-
28	DRAIN

Pin numbers are for dual in-line packages

DG506A

NOTE SLANTED EDGE

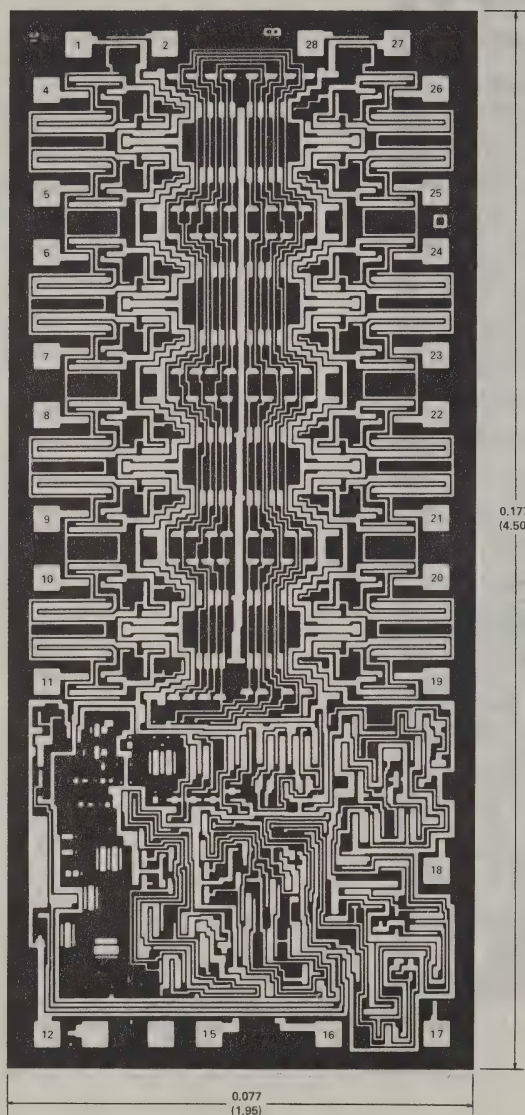


PIN NO.	FUNCTION
1	V+ (SUBSTRATE)
2	DRAIN b
4	SOURCE 8b
5	SOURCE 7b
6	SOURCE 6b
7	SOURCE 5b
8	SOURCE 4b
9	SOURCE 3b
10	SOURCE 2b
11	SOURCE 1b
12	GROUND
13	VREF
15	ADDRESS 2
16	ADDRESS 1
17	ADDRESS 0
18	ENABLE
19	SOURCE 1a
20	SOURCE 2a
21	SOURCE 3a
22	SOURCE 4a
23	SOURCE 5a
24	SOURCE 6a
25	SOURCE 7a
26	SOURCE 8a
27	V-
28	DRAIN a

Pin numbers are for dual in-line packages

DG507



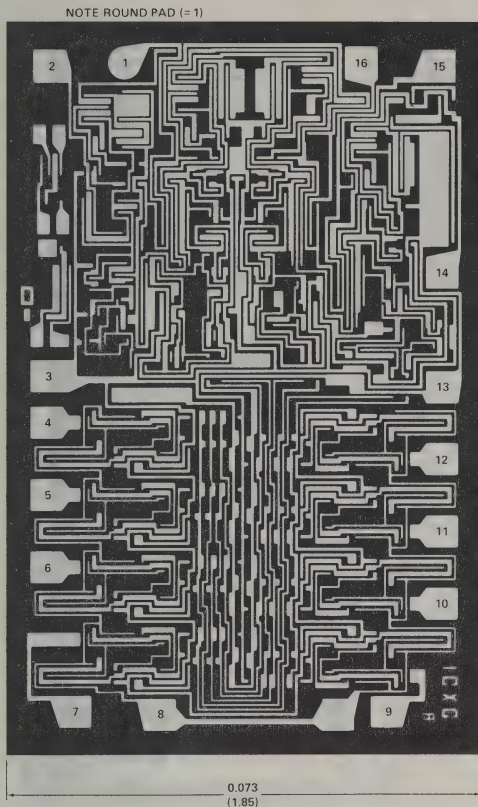


PIN NO.	FUNCTION
1	V+ (SUBSTRATE)
2	DRAIN b
4	SOURCE 8b
5	SOURCE 7b
6	SOURCE 6b
7	SOURCE 5b
8	SOURCE 4b
9	SOURCE 3b
10	SOURCE 2b
11	SOURCE 1b
12	GROUND
15	ADDRESS 2
16	ADDRESS 1
17	ADDRESS 0
18	ENABLE
19	SOURCE 1a
20	SOURCE 2a
21	SOURCE 3a
22	SOURCE 4a
23	SOURCE 5a
24	SOURCE 6a
25	SOURCE 7a
26	SOURCE 8a
27	V-
28	DRAIN a

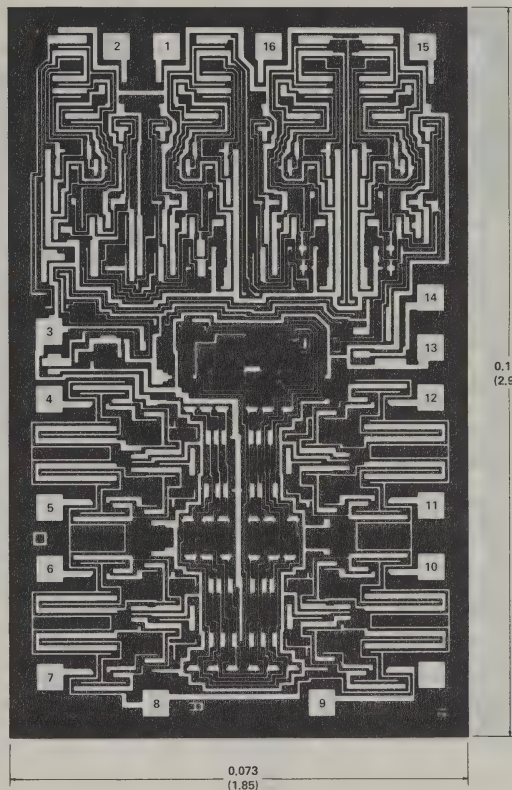
Pin numbers are for dual in-line packages

DG507A





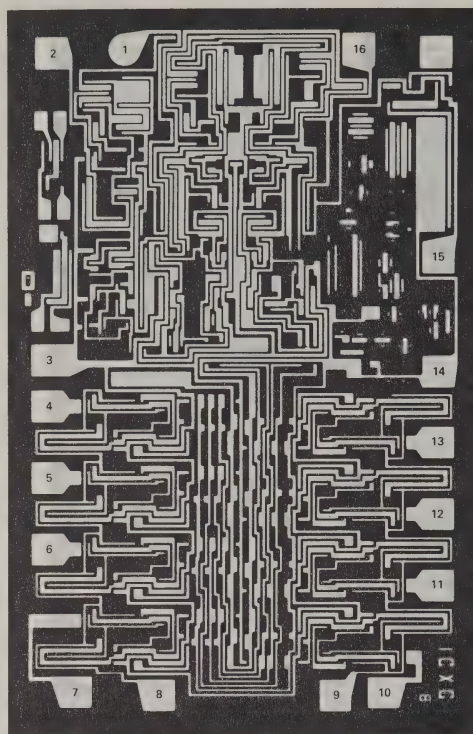
DG508



DG508A

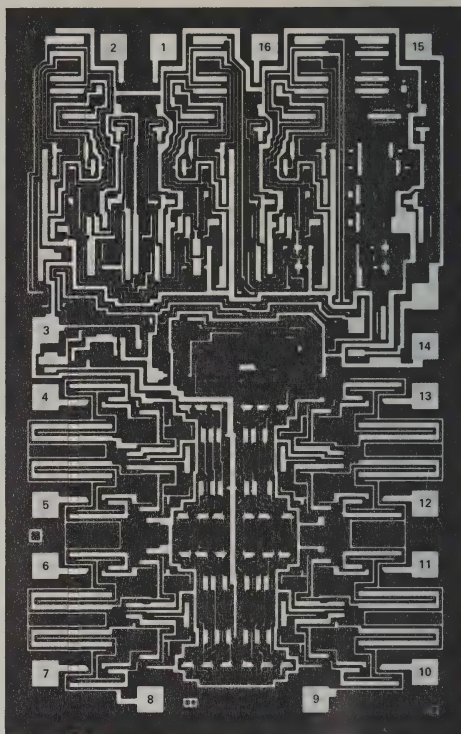
PIN NO.	FUNCTION
1	ADDRESS 0
2	ENABLE
3	V—
4	SOURCE 1
5	SOURCE 2
6	SOURCE 3
7	SOURCE 4
8	DRAIN
9	SOURCE 8
10	SOURCE 7
11	SOURCE 6
12	SOURCE 5
13	V+ (SUBSTRATE)
14	GROUND
15	ADDRESS 2
16	ADDRESS 1

Pin number are for dual in-line packages



0.073  
(1.85)

DG509



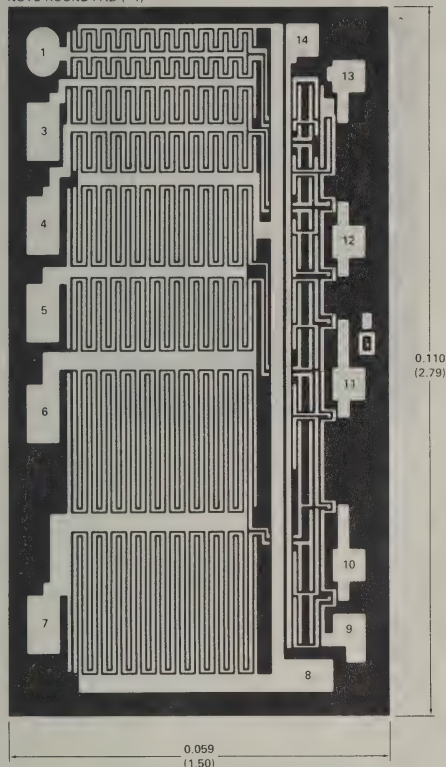
0.073  
(1.85)

DG509A

PIN NO.	FUNCTION
1	ADDRESS 0
2	ENABLE
3	V-
4	SOURCE 1a
5	SOURCE 2a
6	SOURCE 3a
7	SOURCE 4a
8	DRAIN a
9	DRAIN b
10	SOURCE 4b
11	SOURCE 3b
12	SOURCE 2b
13	SOURCE 1b
14	V+ (SUBSTRATE)
15	GROUND
16	ADDRESS 1

Pin numbers are for dual in-line packages

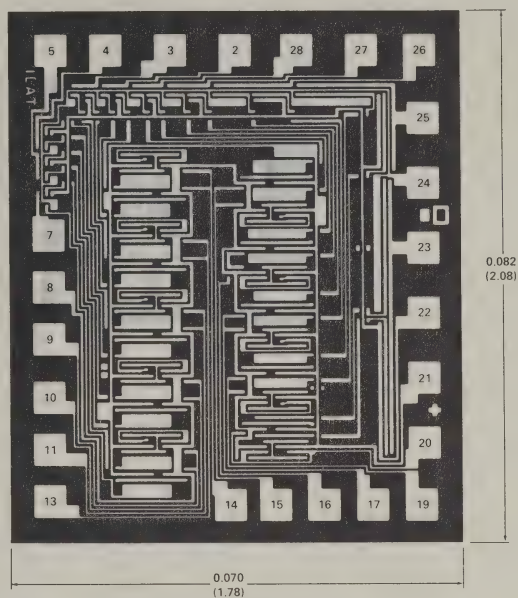
NOTE ROUND PAD (=1)



PIN NO.	FUNCTION
1	SOURCE 4
3	ANALOG GROUND 2
4	SOURCE 3
5	SOURCE 2
6	ANALOG GROUND 1
7	SOURCE 1
8	SUM JCT
9	V+ (SUBSTRATE)
10	B1
11	B2
12	B3
13	B4
14	V-

Pin numbers are for dual in-line packages

DG515

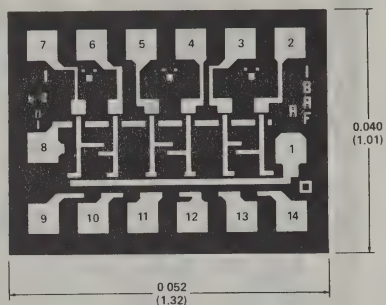


PIN NO.	FUNCTION
2	SOURCE 6
3	SOURCE 7
4	SOURCE 8
5	SOURCE 9
7	SOURCE 10
8	V-
9	B10
10	B9
11	B8
13	B7
14	B6
15	B5
16	B4
17	B3
19	B2
20	B1
21	V+ (SUBSTRATE)
22	SUM JCT
23	S1
24	ANALOG GROUND
25	S2
26	S3
27	S4
28	S5

Pin numbers are for dual in-line packages

DG516

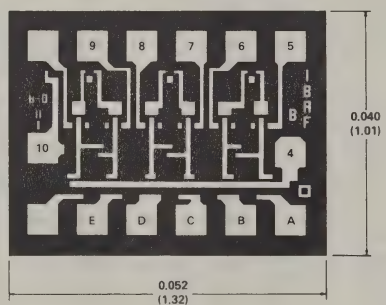




PIN NO.	FUNCTION
1	V- (SUBSTRATE)
2	INPUT 1
3	INPUT 2
4	INPUT 3
5	INPUT 4
6	INPUT 5
7	INPUT 6
8	V <sub>R</sub>
9	OUTPUT 6
10	OUTPUT 5
11	OUTPUT 4
12	OUTPUT 3
13	OUTPUT 2
14	OUTPUT 1

Pin numbers are for dual in-line packages

D123

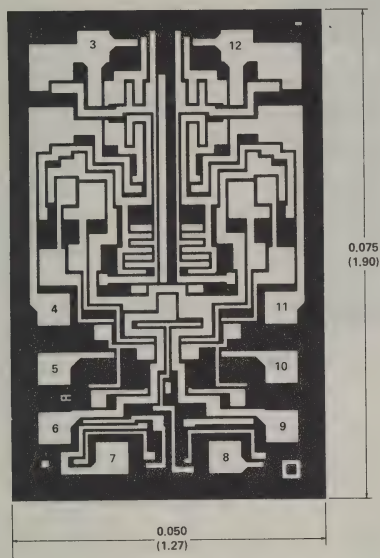


PIN NO.	FUNCTION
1	V- (SUBSTRATE)
2	INPUT 1
3	INPUT 2
4	INPUT 3
5	INPUT 4
6	INPUT 5
7	INPUT 6
8	V <sub>L</sub>
9	OUTPUT 6
10	OUTPUT 5
11	OUTPUT 4
12	OUTPUT 3
13	OUTPUT 2
14	OUTPUT 1

Pin numbers are for dual in-line packages

D125

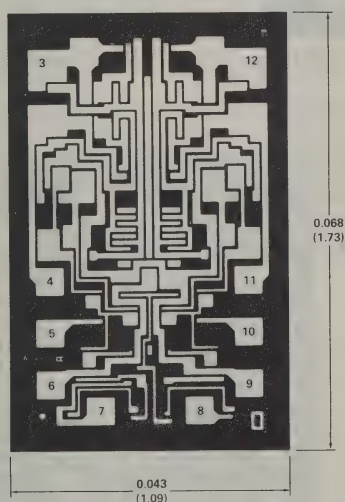




PIN NO.	FUNCTION
1	INPUT 1
2	INPUT 2
3	INPUT 3
4	INPUT 4
5	INPUT 5
6	INPUT 6
7	INPUT 7
8	$V_R$
9	$V_-$ (SUBSTRATE)
10	OUTPUT 4
11	OUTPUT 3
12	OUTPUT 2
13	OUTPUT 1
14	$V_L$

Pin numbers are for dual in line packages

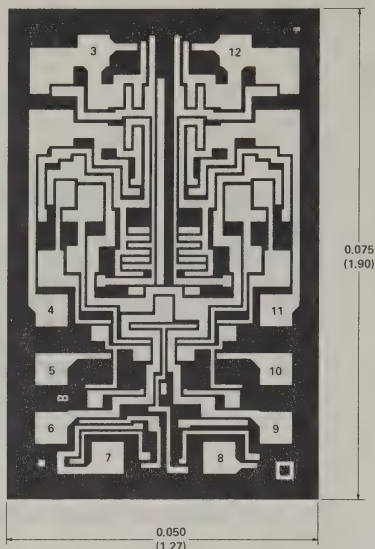
D129



PIN NO.	FUNCTION
3	OUT 1
4	OUT 1
5	INPUT 1
6	$V_+$
7	$V_L$
8	$V_R$
9	$V_-$ (SUBSTRATE)
10	INPUT 2
11	OUT 2
12	OUT 2

Pin numbers are for dual in-line packages

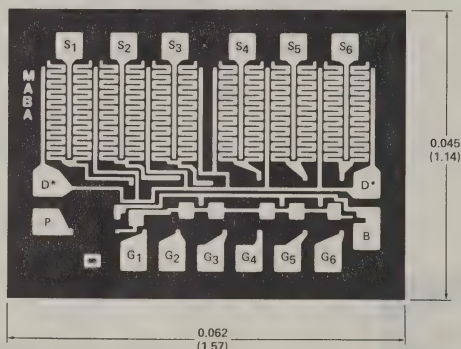
D139



PAD NO.	FUNCTION
3	$\overline{\text{OUT}}_1$
4	$\text{OUT}_1$
5	$\text{IN}_1$
6	$\text{V}+$
7	$\text{V}_\text{L}$
8	$\text{V}_\text{R}$
9	$\text{V}-$
10	$\text{IN}_2$
11	$\overline{\text{OUT}}_2$
12	$\text{OUT}_2$

Substrate =  $\text{V}-$

D169

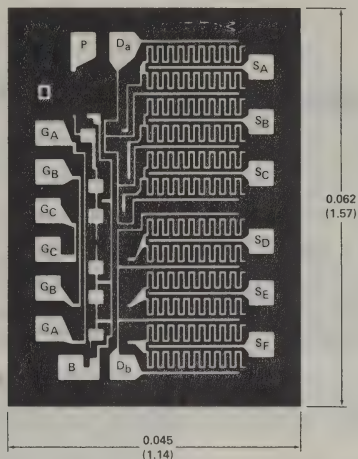


\*Both "D" pads are electrically common. Either can be used for drain contact.

PAD	G115 DUAL IN-LINE PACKAGE PIN NO.	G116 DUAL IN-LINE PACKAGE PIN NO.	G117 FLAT PACK PIN NO.	G118 DUAL IN-LINE PACKAGE PIN NO.	G124 DUAL IN-LINE PACKAGE PIN NO.	FUNCTION
$\dagger\text{G}_1$	2	2	3	1	2	GATE 1
$\dagger\text{G}_2$	3	3	4	2	3	GATE 2
$\dagger\text{G}_3$	4	4	5	3	4	GATE 3
$\dagger\text{G}_4$	5	5	6	4	5	GATE 4
$\dagger\text{G}_5$	6	6	7	5	NOT USED	GATE 5
$\dagger\text{G}_6$	7	NOT USED	2	6	NOT USED	GATE 6
B	9	8	8	7	8	BODY (SUBSTRATE) $\text{V}+$
D	16	14	NOT USED	8	14	
$\text{S}_6$	10	NOT USED	14**	9	NOT USED	DRAIN
$\text{S}_5$	11	9	9	10	NOT USED	SOURCE 6
$\text{S}_4$	12	10	10	11	10	SOURCE 5
$\text{S}_3$	13	11	11	12	11	SOURCE 4
$\text{S}_2$	14	12	12	13	12	SOURCE 3
$\text{S}_1$	15	13	13	14	13	SOURCE 2
P	1	1	1	TIED TO SUBSTRATE	1	SOURCE 1
						PULL UP GATE INPUT

$\dagger$  Any unused gates should be connected to the substrate  $\text{V}+$ ; unused sources can be left open

\*\* The G117 uses the  $\text{S}_6$  pad as the drain output (pin 14 on package).

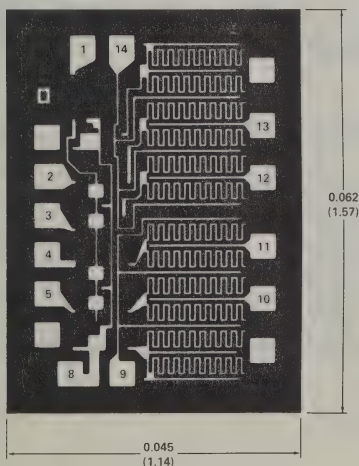


PAD	G119		G122	
	FLAT PACK PIN NO.	FUNCTION	FLAT PACK PIN NO.	FUNCTION
G <sub>a</sub>	3	GATE 1	3	GATE 2
G <sub>b</sub>	4	GATE 3	†NOT USED	GATE 1
G <sub>c</sub>	5	GATE 5		
G <sub>b</sub>				
G <sub>a</sub>			5	
B	6	BODY (SUBSTRATE V+)	8	BODY (SUBSTRATE V+)
D <sub>b</sub>	7	DRAIN 2	9	DRAIN 1
S <sub>F</sub>	9	SOURCE 2	10	SOURCE 1
S <sub>E</sub>	10	SOURCE 4	11	SOURCE 2
S <sub>D</sub>	11	SOURCE 6	NOT USED	
S <sub>C</sub>	12	SOURCE 5	NOT USED	
S <sub>B</sub>	13	SOURCE 3	12	SOURCE 3
S <sub>A</sub>	14	SOURCE 1	13	SOURCE 4
D <sub>a</sub>	1	DRAIN 1	14	DRAIN 2
P	2	PULL UP GATE INPUT	1	PULL UP GATE INPUT

† Any unused gates should be connected to the substrate V+; unused sources can be left open.

G119

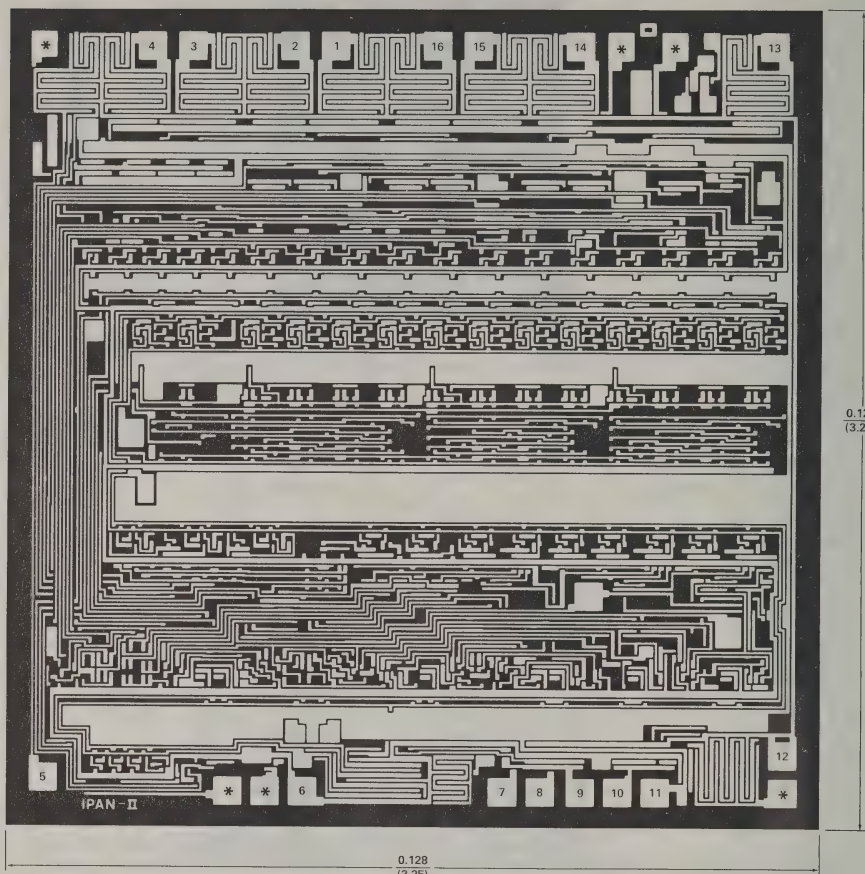
G122



PIN NO.	FUNCTION
1	P (PULL UP GATE INPUT)
2	GATE 1
3	GATE 2
4	GATE 3
5	GATE 4
8	BODY (SUBSTRATE) V+
9	DRAIN 2
10	SOURCE 4
11	SOURCE 3
12	SOURCE 2
13	SOURCE 1
14	DRAIN 1

Pin numbers are for dual in-line packages.

G123



PAD NO.	FUNCTION
1	D <sub>1</sub>
2	D <sub>2</sub>
3	D <sub>3</sub>
4	D <sub>4</sub>
5	SIGN
6	V <sub>SS</sub>
7	CLOCK IN
8	COMP
9	U/D
10	M/Z
11	V <sub>2</sub>
12	GND
13	B <sub>4</sub>
14	B <sub>3</sub>
15	B <sub>2</sub>
16	B <sub>1</sub>

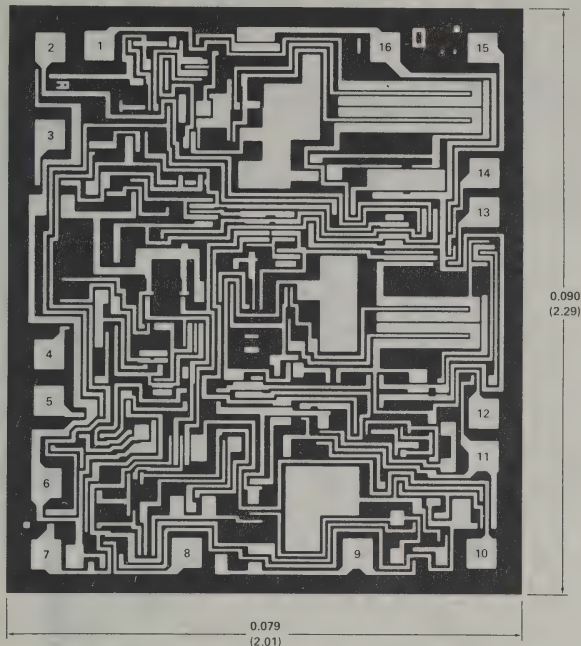
Substrate = V<sub>SS</sub>

\* Leave unused pads floating

LD110

ALL DIMENSIONS IN INCHES  
(ALL DIMENSIONS IN MILLIMETERS)

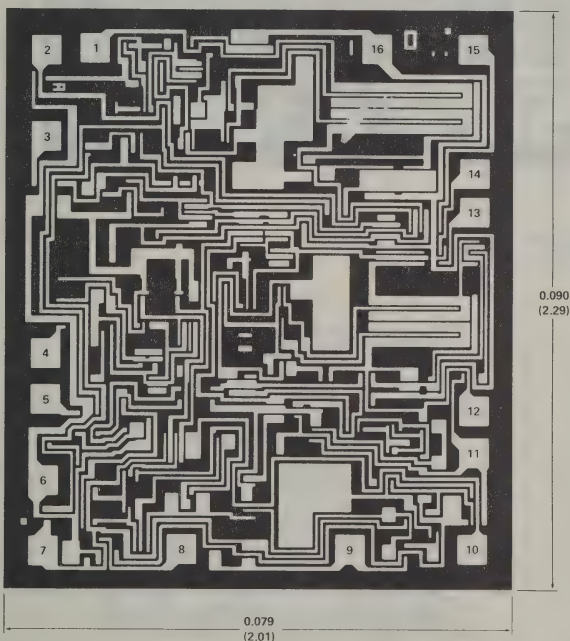




PAD NO.	FUNCTION
1	BUFF OUT
2	HI-Q GND
3	M/Z
4	U/D
5	COMP
6	V <sub>2</sub>
7	GND
8	REF OUT
9	INT IN
10	V <sub>REF</sub>
11	INT OUT
12	AZ OUT
13	AZ FILTER
14	AZ IN
15	V <sub>IN</sub>
16	V <sub>1</sub>

Substrate = V<sub>2</sub>

LD111A

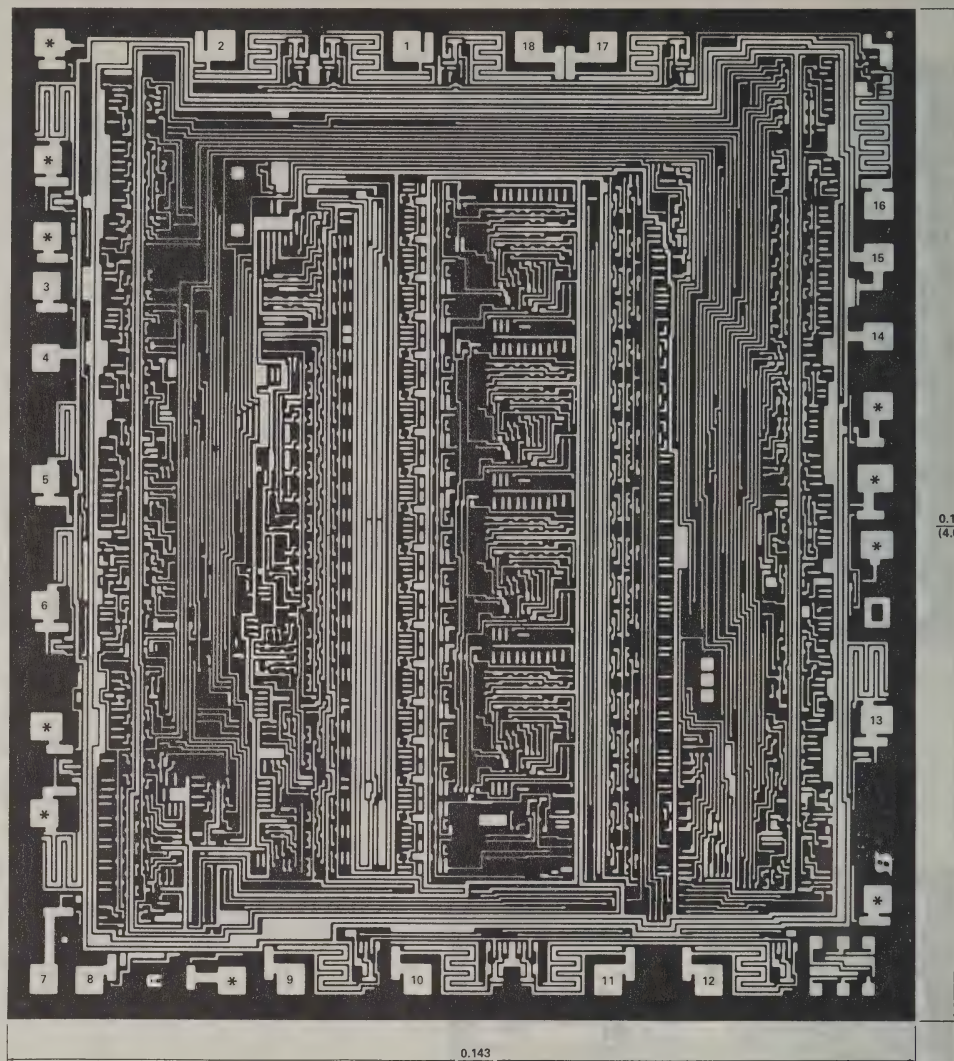


PAD NO.	FUNCTION
1	BUFF OUT
2	HI-Q GND
3	M/Z
4	U/D
5	COMP
6	V <sup>-</sup>
7	ANALOG GND
8	REF OUT
9	INT IN
10	V <sub>REF</sub>
11	INT OUT
12	AZ OUT
13	AZ FILTER
14	AZ IN
15	V <sub>IN</sub>
16	V <sup>+</sup>

Substrate = V<sup>-</sup>

LD120

ALL DIMENSIONS IN INCHES  
(ALL DIMENSIONS IN MILLIMETERS)



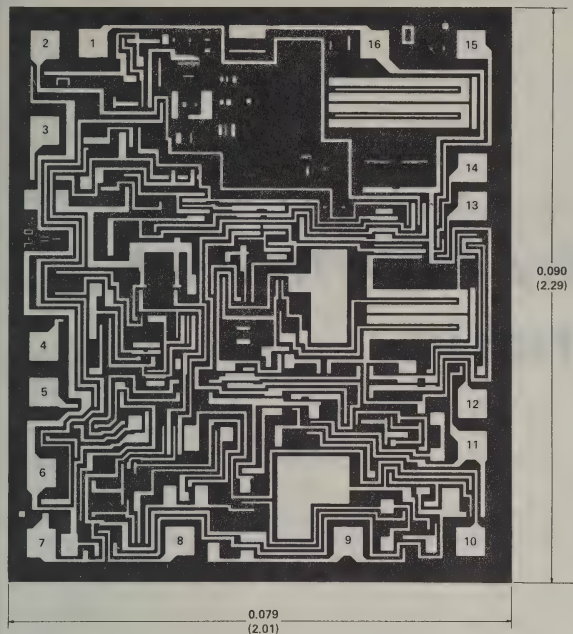
PAD NO.	FUNCTION
1	D <sub>2</sub>
2	D <sub>1</sub>
3	COMP
4	GND
5	U/D
6	M/Z
7	START
8	OSC
9	B <sub>0</sub>
10	B <sub>1</sub>
11	B <sub>2</sub>
12	B <sub>3</sub>
13	SIGN/OR/UR
14	V <sub>SS</sub>
15	V <sub>DD</sub>
16	D <sub>5</sub>
17	D <sub>4</sub>
18	D <sub>3</sub>

Substrate = V<sub>SS</sub>

\* Leave unused pads floating

ALL DIMENSIONS IN INCHES  
(ALL DIMENSIONS IN MILLIMETERS)

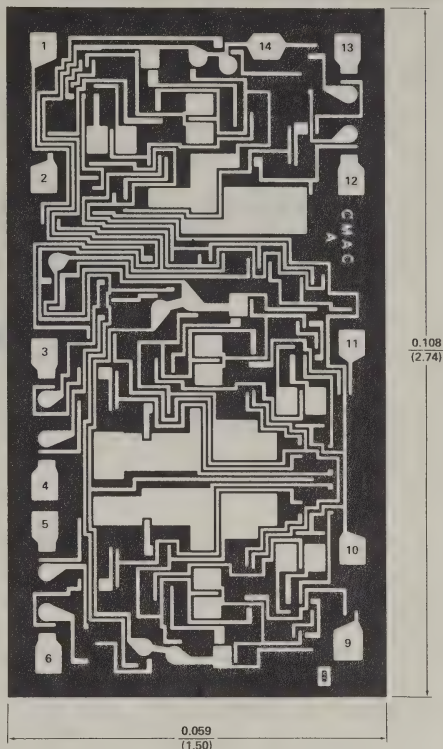
LD121A



PAD NO.	FUNCTION
1	BUFF IN
2	HI-Q GND
3	M/Z
4	U/D
5	COMP
6	V -
7	ANALOG GND
8	REFOUT
9	INT IN
10	VREF
11	INT OUT
12	AZ OUT
13	AZ FILTER
14	AZ IN
15	V <sub>IN</sub>
16	V +

Substrate = V -

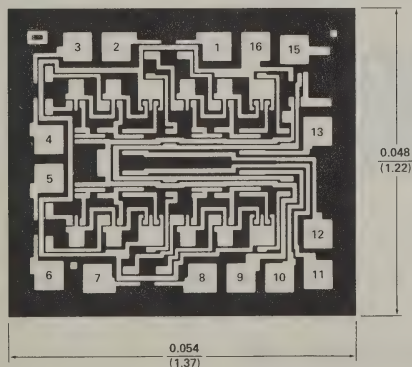
LD122



PAD NO.	FUNCTION
1	SET
2	OUT 1
3	-IN2
4	+IN2
5	+IN3
6	-IN3
9	OUT3
10	-V <sub>S</sub>
11	OUT2
12	+IN1
13	-IN1
14	+V <sub>S</sub>

Substrate = -V<sub>S</sub>

L144



PAD NO.	FUNCTION
1	+IN <sub>1</sub>
2	-IN <sub>1</sub>
3	+IN <sub>2</sub>
4	-IN <sub>2</sub>
5	-IN <sub>3</sub>
6	+IN <sub>3</sub>
7	-IN <sub>4</sub>
8	+IN <sub>4</sub>
9	-V
10	OUT <sub>4</sub>
11	OUT <sub>3</sub>
12	OUT <sub>2</sub>
13	OUT <sub>1</sub>
15	I <sub>SET</sub>
16	+V

Substrate = -V

L161

ALL DIMENSIONS IN INCHES  
(ALL DIMENSIONS IN MILLIMETERS)



# **Die Topography Information Multichip**



# Multichip

### Die Diagrams/Dimensions

These negative image photos are of the metallization pattern. Scale is  $\approx 32\times$ . Bonding pads are 4 mil (0.10 mm) square, glass-free aluminum metallization. Pad identification numbers correspond to pin numbers for the dual-in-line package on data sheets. The "geometry" is an alpha code used in the factory for identification.

The following pages contain layout, die dimensions and pad identification.



# Die Topography Information (Continued)

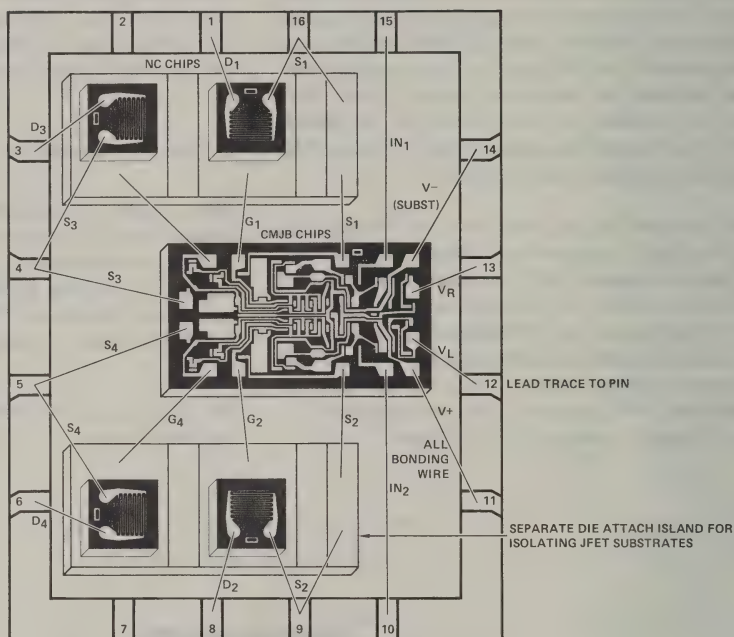


Figure 2. DG190 JFET Analog Switch

NOTE: Die Topography is *for reference only*

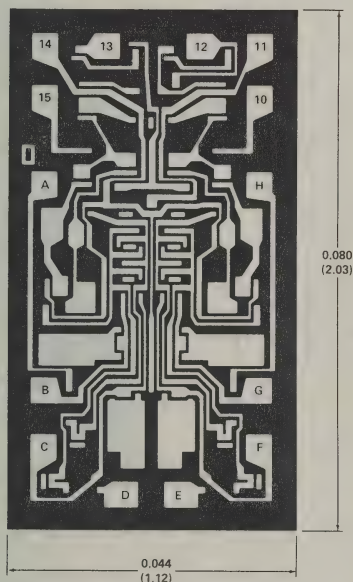
**CMJA1000 — DRIVER CHIP CHARACTERISTICS**

All parameters are specified under the following conditions:  $V_+ = +15\text{ V}$ ,  $V_- = -15\text{ V}$ ,  $V_R = 0\text{ V}$ ,  $V_L = 5\text{ V}$ ,  $T_A = 25^\circ\text{C}$ .

**DC PARAMETERS**

Characteristics			Min	Max	Unit	Test Conditions
1	$I_{INL}$	Input Current Input Voltage Low		-250	$\mu\text{A}$	$V_{IN} = 0\text{ V}$
2	$I_{INH}$	Input Current Input Voltage High		20	$\mu\text{A}$	$V_{IN} = 5\text{ V}$
3	$I_L$	Logic Supply Current		4.5	mA	$V_{IN} = 0\text{ V}$
4				4.5		$V_{IN} = 5\text{ V}$
5	$I_R$	Reference Supply Current		-2	mA	$V_{IN} = 0\text{ V}$
6				-2		$V_{IN} = 5\text{ V}$
7	$I_-$	Negative Supply Current		-5.5	mA	$V_{IN} = 0\text{ V}$
8				-4		$V_{IN} = 5\text{ V}$
9	$I_+$	Positive Supply Current		3	mA	$V_{IN} = 0\text{ V}$
10				0.1		$V_{IN} = 5\text{ V}$

$V_{IN} = 0.8\text{ V}$  or  $2.0\text{ V}$



PAD NO.	FUNCTION
10	INPUT 2
11	$V_+$
12	$V_L$
13	$V_R$
14	$V_-$ (SUBSTRATE)
15	INPUT 1

INTERCHIP PAD CONNECTIONS	
A	FROM JFET 1, SOURCE
B	TO JFET 1, GATE
C	TO JFET 3, GATE
D	FROM JFET 3, SOURCE
E	FROM JFET 4, SOURCE
F	TO JFET 4, GATE
G	TO JFET 2, GATE
H	FROM JFET 2, SOURCE

CMJA1000 is used for following devices:

DEVICE	JFET USED	NO. OF JFETs
DG183	NIP1000	4
DG184	NC1000	4
DG185	NC2000	4
DG284	NH1000	4

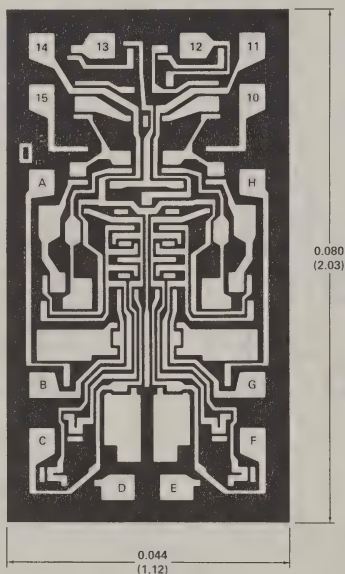
**CMJB1000 — DRIVER CHIP CHARACTERISTICS**

All parameters are specified under the following conditions:  $V_+ = 15\text{ V}$ ,  $V_- = -15\text{ V}$ ,  $V_R = 0\text{ V}$ ,  $V_L = 5\text{ V}$ ,  $T_A = 25^\circ\text{C}$ .

**DC PARAMETERS**

Characteristics			Min	Max	Unit	Test Conditions
1	$I_{INL}$	Input Current Input Voltage Low		-250	$\mu\text{A}$	$V_{IN} = 0\text{ V}$
2	$I_{INH}$	Input Current Input Voltage High		20	$\mu\text{A}$	$V_{IN} = 5\text{ V}$
3	$I_L$	Logic Supply Current		4.5	mA	$V_{IN} = 0\text{ V}$
4				4.5		$V_{IN} = 5\text{ V}$
5	$I_R$	Reference Supply Current		-2	mA	$V_{IN} = 0\text{ V}$
6				-2		$V_{IN} = 5\text{ V}$
7	$I_-$	Negative Supply Current		-5	mA	$V_{IN} = 0\text{ V}$
8				-5		$V_{IN} = 5\text{ V}$
9	$I_+$	Positive Supply Current		1.5	mA	$V_{IN} = 0\text{ V}$
10				1.5		$V_{IN} = 5\text{ V}$

$V_{IN} = 0.8\text{ V}$  or  $2.0\text{ V}$



PAD NO.	FUNCTION
10	INPUT 2
11	$V_+$
12	$V_L$
13	$V_R$
14	$V_-$ (SUBSTRATE)
15	INPUT 1

**INTERCHIP PAD CONNECTIONS****With 2 JFETs:**

A	NO CONNECTION
B	NO CONNECTION
C	TO JFET 2, GATE
D	FROM JFET 2, SOURCE
E	FROM JFET 1, SOURCE
F	TO JFET 1, GATE
G	NO CONNECTION
H	NO CONNECTION

**With 4 JFETs:**

A	FROM JFET 1, SOURCE
B	TO JFET 1, GATE
C	TO JFET 3, GATE
D	FROM JFET 3, SOURCE
E	FROM JFET 4, SOURCE
F	TO JFET 4, GATE
G	TO JFET 2, GATE
H	FROM JFET 2, SOURCE

CMJB1000 is used for following devices:

DEVICE	JFET USED	NO. OF JFETs
DG180	NIP1000	2
DG181	NC1000	2
DG182	NC2000	2
DG189	NIP1000	4
DG190	NC1000	4
DG191	NC2000	4
DG281	NH1000	2
DG290	NH1000	4

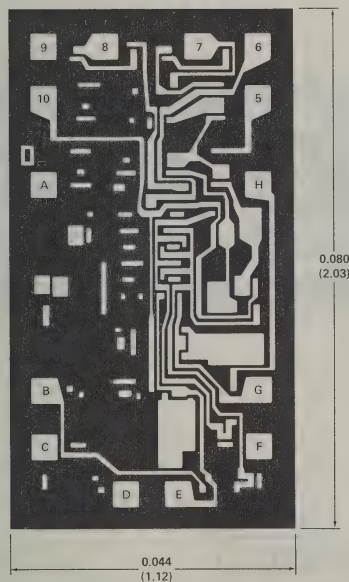


**CMJC1000 — DRIVER CHIP CHARACTERISTICS**

All parameters are specified under the following conditions:  $V_+ = 15\text{ V}$ ,  $V_- = -15\text{ V}$ ,  $V_R = 0\text{ V}$ ,  $V_L = 5\text{ V}$ ,  $T_A = 25^\circ\text{C}$ .

**DC PARAMETERS**

Characteristics			Min	Max	Unit	Test Conditions
1	$I_{INL}$	Input Current Input Voltage Low		-250	$\mu\text{A}$	$V_{IN} = 0\text{ V}$
2	$I_{INH}$	Input Current Input Voltage High		10	$\mu\text{A}$	$V_{IN} = 5\text{ V}$
3	$I_L$	Logic Supply Current		3.2	mA	$V_{IN} = 0\text{ V}$
4				3.2		$V_{IN} = 5\text{ V}$
5	$I_R$	Reference Supply Current		-2	mA	$V_{IN} = 0\text{ V}$
6				-2		$V_{IN} = 5\text{ V}$
7	$I_-$	Negative Supply Current		-3	mA	$V_{IN} = 0\text{ V}$
8				-3		$V_{IN} = 5\text{ V}$
9	$I_+$	Positive Supply Current		0.8	mA	$V_{IN} = 0\text{ V}$
10				0.8		$V_{IN} = 5\text{ V}$



PAD NO.	FUNCTION
5	INPUT 1
6	$V_+$
7	$V_L$
8	$V_R$
9	NOT CONNECTED
10	$V_-$ (SUBSTRATE)

INTERCHIP PAD CONNECTIONS	
A	NOT CONNECTED
B	FROM JFET 2, SOURCE
C	NOT CONNECTED
D	NOT CONNECTED
E	TO JFET 2, GATE
F	NOT CONNECTED
G	TO JFET 1, GATE
H	FROM JFET 1, SOURCE

CMJC1000 is used for following devices:

DEVICE	JFET USED	NO. OF JFETs
DG186	NIP1000	2
DG187	NC1000	2
DG188	NC2000	2
DG287	NH1000	2

**LODC1000 — DRIVER CHIP CHARACTERISTICS**

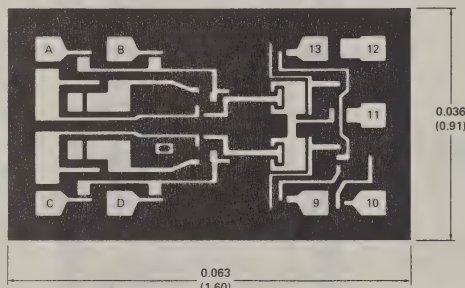
All parameters are specified under the following conditions:  $V_+ = +12\text{ V}$ ,  $V_- = -18\text{ V}$ ,  $V_R = 0\text{ V}$ ,  $T_A = 25^\circ\text{C}$ .

**DC PARAMETERS**

Characteristics			Min	Max	Unit	Test Conditions
1	$I_{INL}$	Input Current Input Voltage Low		0.1	$\mu\text{A}$	$V_{IN} = 0.8\text{ V}$
2	$I_{INH}$	Input Current Input Voltage High		100	$\mu\text{A}$	$V_{IN} = 2.5\text{ V}$
3	$I_+$	Positive Supply Current		3.3	$\mu\text{A}$	$V_{IN} = 2.5\text{ V}$ , One Channel On
4	$I_-$	Negative Supply Current		-2.0	$\mu\text{A}$	
5	$I_R$	Reference Supply Current		-1.5	$\mu\text{A}$	
6	$I_+$	Positive Supply Current		25	$\mu\text{A}$	Both $V_{IN} = 0\text{ V}$ , All Channels Off
7	$I_-$	Negative Supply Current		-25	$\mu\text{A}$	
8	$I_R$	Reference Supply Current		-25	$\mu\text{A}$	

**NOTES:**

- $V_{IN}$  must be a step function with a minimum rise and fall rate of  $1\text{ V}/\mu\text{S}$ .
- The supply voltage condition of  $+12\text{ V}/-18\text{ V}$  is standard test condition. Specs will also be met with  $+15\text{ V}/-15\text{ V}$  supplies, but are not tested.



PAD NO.	FUNCTION
9	INPUT 1
10	$V_R$
11	$V_+$
12	$V_-$ (SUBSTRATE)
13	INPUT 2

INTERCHIP CONNECTIONS	
With 2 JFETs:	
A	TO GATE 2
B	NO CONNECTION
C	TO GATE 1
D	NO CONNECTION
With 4 JFETs:	
A	TO GATE 4
B	TO GATE 2
C	TO GATE 3
D	TO GATE 1

LODC1000 is used for following devices:

DEVICE	JFET USED	NO. OF JFETs
DG126	NC2000	4
DG129	NC1000	4
DG133	NC1000	2
DG134	NC2000	2
DG140	NIP1000	4
DG141	NIP1000	2
DG151	NIP1000	2
DG152	NC1000	2
DG153	NIP1000	4
DG154	NC1000	4

## LODF1000 — DRIVER CHIP CHARACTERISTICS

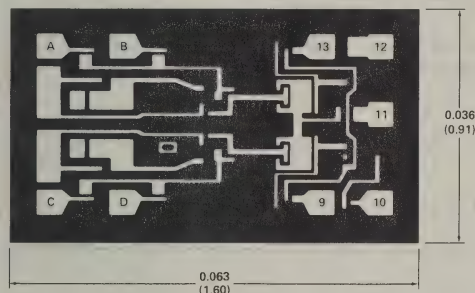
All parameters are specified under the following conditions:  $V_+ = +12\text{ V}$ ,  $V_- = -18\text{ V}$ ,  $V_R = 0\text{ V}$ ,  $V_{IN2} = 2.5\text{ V}$  unless otherwise noted,  $T_A = 25^\circ\text{C}$ .

## DC PARAMETERS

Characteristics			Min	Max	Unit	Test Conditions
1	$I_{INL1}$	Input Current		0.1	$\mu\text{A}$	$V_{IN1} = 2\text{ V}$ , $V_{IN2} = 2.5\text{ V}$
	$I_{INL2}$	Input Voltage Low		0.1		$V_{IN1} = 2.5\text{ V}$ , $V_{IN2} = 2\text{ V}$
2	$I_{INH1}$	Input Current		100	$\mu\text{A}$	$V_{IN1} = 3\text{ V}$ , $V_{IN2} = 2.5\text{ V}$
	$I_{INH2}$	Input Voltage High		100		$V_{IN1} = 2.5\text{ V}$ , $V_{IN2} = 3\text{ V}$
3	$I_+$	Positive Supply Current		4.5	$\mu\text{A}$	$V_{IN1} = 2\text{ V}$ or $V_{IN1} = 3\text{ V}$ , One Channel On
4	$I_-$	Negative Supply Current		-2.2	$\mu\text{A}$	
5	$I_R$	Reference Supply Current		-2.4	$\mu\text{A}$	
6	$I_+$	Positive Supply Current		25	$\mu\text{A}$	$V_{IN1} = V_{IN2} = 0.8\text{ V}$ , All Channels Off
7	$I_-$	Negative Supply Current		-25	$\mu\text{A}$	
8	$I_R$	Reference Supply Current		-25	$\mu\text{A}$	

## NOTES:

- $V_{IN}$  must be a step function with a minimum rise and fall rate of  $1\text{ V}/\mu\text{S}$ .
- The supply voltage condition of  $+12\text{ V}/-18\text{ V}$  is standard test condition. Specs will also be met with  $+15\text{ V}/-15\text{ V}$  supplies, but are not tested.



PAD NO.	FUNCTION
9	INPUT 1
10	$V_R$
11	$V_+$
12	$V_-$ (SUBSTRATE)
13	INPUT 2

INTERCHIP CONNECTIONS	
With 2 JFETs:	
A	TO GATE 2
B	NO CONNECTION
C	TO GATE 1
D	NO CONNECTION
With 4 JFETs:	
A	TO GATE 4
B	TO GATE 2
C	TO GATE 3
D	TO GATE 1

LODF1000 is used for following devices:

DEVICE	JFET USED	NO. OF JFETs
DG139	NC1000	4
DG142	NC2000	4
DG143	NC2000	2
DG144	NC1000	2
DG145	NIP1000	4
DG146	NIP1000	2
DG161	NIP1000	2
DG162	NC1000	2
DG163	NIP1000	4
DG164	NC1000	4



NC1000 JFET SWITCH CHARACTERISTICS

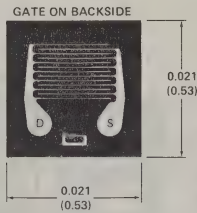
DC PARAMETERS  $T_A = 25^{\circ}\text{C}$

Characteristics			Min	Max	Unit	Test Conditions
1	$BV_{GDS}$	Gate-Drain Breakdown Voltage	-35		V	$I_G = -1\text{ }\mu\text{A}$
2	$I_{D(off)}$	Drain Cut Off Current		1.0	nA	$V_{DS} = 22\text{ V}, V_{GS} = -6.2\text{ V}$
3	$I_{S(off)}$	Source Cut Off Current		1.0	nA	$V_{DS} = 22\text{ V}, V_{GS} = -6.2\text{ V}$
4	$r_{DS(on)}$	Drain Source-ON Resistance		30	$\Omega$	$V_{GS} = 0\text{ V}, G_{DS} = 0.2\text{ V}$

NC2000 JFET SWITCH CHARACTERISTICS

DC PARAMETERS  $T_A = 25^{\circ}\text{C}$

Characteristics			Min	Max	Unit	Test Conditions
1	$BV_{GDS}$	Gate-Drain Breakdown Voltage	-35		V	$I_G = -1\text{ }\mu\text{A}$
2	$I_{D(off)}$	Drain Cut Off Current		1.0	nA	$V_{DS} = 22\text{ V}, V_{GS} = -3.9\text{ V}$
3	$I_{S(off)}$	Source Cut Off Current		1.0	nA	$V_{DS} = 22\text{ V}, V_{GS} = -3.9\text{ V}$
4	$r_{DS(on)}$	Drain Source-ON Resistance		75	$\Omega$	$V_{GS} = 0\text{ V}, G_{DS} = 0.2\text{ V}$



INTERCHIP CONNECTIONS	FUNCTION
S	SOURCE
D	DRAIN

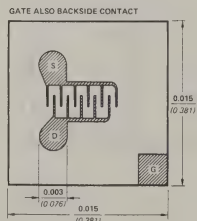
Gate is on backside of chip

NC1000/NC2000

NH1000 JFET SWITCH CHARACTERISTICS

DC PARAMETERS  $T_A = 25^{\circ}\text{C}$

Characteristics			Min	Max	Unit	Test Conditions
1	$BV_{GDS}$	Gate-Drain Breakdown Voltage	-33		V	$I_G = -1\text{ }\mu\text{A}$
2	$I_{D(off)}$	Drain Cut Off Current		200	pA	$V_{DS} = 22\text{ V}, V_{GS} = -6.2\text{ V}$
3	$I_{S(off)}$	Source Cut Off Current		200	pA	$V_{DS} = 22\text{ V}, V_{GS} = -6.2\text{ V}$
4	$r_{DS(on)}$	Drain Source-ON Resistance		300	$\Omega$	$V_{GS} = 0\text{ V}, G_{DS} = 0.2\text{ V}$



INTERCHIP PAD CONNECTIONS	FUNCTION
S	SOURCE
D	DRAIN
G	GATE

300  $\Omega$   
JFET SWITCH CHIP

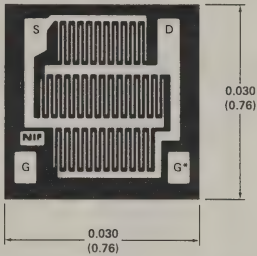


NIP1000 JFET SWITCH CHARACTERISTICS

DC PARAMETERS  $T_A = 25^{\circ}\text{C}$

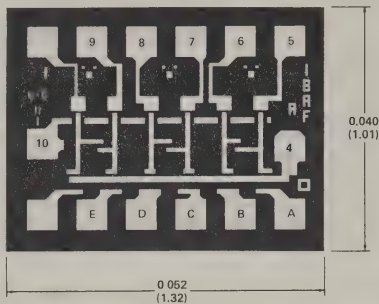
Characteristics			Min	Max	Unit	Test Conditions
1	$BV_{GDS}$	Gate-Drain Breakdown Voltage	-33		V	$I_G = -1\text{ }\mu\text{A}$
2	$I_{D(off)}$	Drain Cut Off Current		10	nA	$V_{GS} = -6.2\text{ V}, V_{DS} = 22\text{ V}$
3	$I_{S(off)}$	Source Cut Off Current		10	nA	$V_{GS} = -6.2\text{ V}, V_{DS} = -22\text{ V}$
4	$r_{DS(on)}$	Drain Source		10	$\Omega$	$V_{GS} = 0\text{ V}, G_{DS} = 0.2\text{ V}$

BOTH GATE PADS ARE COMMON,  
GATE ALSO ON BACKSIDE



INTERCHIP PAD CONNECTIONS	FUNCTION
S	SOURCE
D	DRAIN
G	GATE

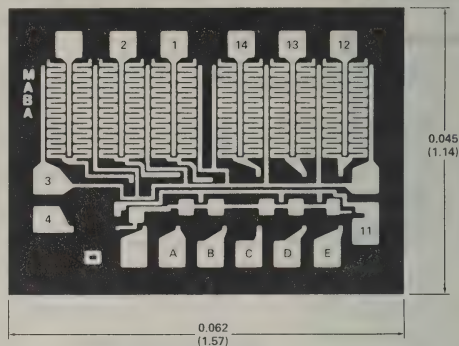
\* Either gate pad can be used,  
backside is also gate



PIN NO.	FUNCTION
4	V- (SUBSTRATE)
5	INPUT 1
6	INPUT 2
7	INPUT 3
8	INPUT 4
9	INPUT 5
10	V <sub>R</sub>

INTERCHIP PAD CONNECTIONS	
A	TO GATE 1
B	TO GATE 2
C	TO GATE 3
D	TO GATE 4
E	TO GATE 5

DRIVER CHIP



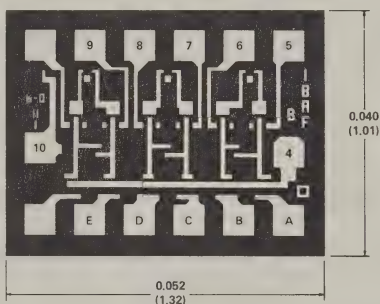
PIN NO.	FUNCTION
1	SOURCE 2
2	SOURCE 1
3	DRAIN
4	V-
11	V+ (SUBSTRATE)
12	SOURCE 5
13	SOURCE 4
14	SOURCE 3

INTERCHIP PAD CONNECTIONS	
A	GATE 1
B	GATE 2
C	GATE 3
D	GATE 4
E	GATE 5

Pin numbers are for dual in-line packages

MOS SWITCH CHIP

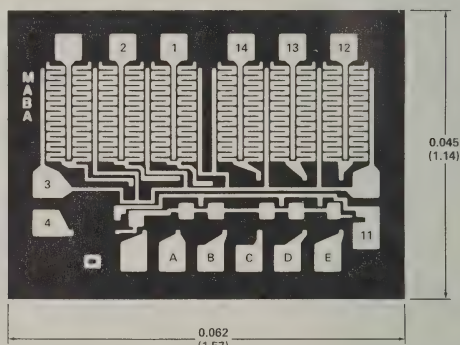
DG123



PIN NO.	FUNCTION
4	V- (SUBSTRATE)
5	INPUT 1
6	INPUT 2
7	INPUT 3
8	INPUT 4
9	INPUT 5
10	V <sub>L</sub>

INTERCHIP PAD CONNECTIONS	
A	TO GATE 1
B	TO GATE 2
C	TO GATE 3
D	TO GATE 4
E	TO GATE 5

DRIVER CHIP



PIN NO.	FUNCTION
1	SOURCE 2
2	SOURCE 1
3	DRAIN
4	V-
11	V+ (SUBSTRATE)
12	SOURCE 5
13	SOURCE 4
14	SOURCE 3

INTERCHIP PAD CONNECTIONS	
A	GATE 1
B	GATE 2
C	GATE 3
D	GATE 4
E	GATE 5

Pin numbers are for dual in-line packages

MOS SWITCH CHIP

DG125



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# Burn-In Pin Connections

The following table lists the standard Burn-In Pin Connections for most Siliconix Integrated Circuits. Devices are listed in Alpha-Numerical order according to package type. Following the tables are two examples illustrating Burn-In Pin Connections for different switches and packages.

Part Type	Package Type*	Pins																	
		1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18
D129	P/L	(7)	(7)	(7)	GND	(7)	(7)	10K→+5 V	GND	−30 V	(13)	(13)	(13)	10K→+5 V	+5 V				
D123/ D125	P/L	−30 V	(14)	(14)	(14)	(14)	(14)	(14)	(14)	(14)	(14)	(14)	(14)	10K→GND					
D139 D169	P/L	—	—	10K→Pin 4	10K→Pin 3	+5 V	+10 V	+5 V	GND	−20 V	GND	10K→Pin 12	10K→Pin 11	—	—				
DG123	P/L	GND	GND	GND	−20 V	4.7K→+5 V	4.7K→+5 V	4.7K→+5 V	4.7K→+5 V	4.7K→+5 V	GND	+5 V	GND	GND	GND				
DG125	P/L	GND	GND	GND	−20 V	GND	GND	GND	GND	GND	+5 V	+5 V	GND	GND	GND				
DG126 DG129 DG133 DG134 DG139 DG140 DG141 DG142 DG143 DG144 DG145 DG146 DG151 DG152 DG153 DG154 DG161 DG162 DG163 DG164	P/L	10K→GND	+10 V	10K→GND	—	+10 V	10K→GND	10K→GND	+10 V	GND	GND	+10 V	−20 V	GND	+10 V				
DG172	P/L	To Pin 14	GND	GND	—	−20 V	GND	+5 V	+5 V	+5 V	+5 V	GND	+5 V	To Pin 14	7.5K→−20 V				
DG180 DG181 DG182 DG186 DG187 DG188 DG281	A	+15 V	10K→GND	GND	+15 V	+5 V	GND	−15 V	GND	10K→GND	+15 V								
DG180 DG181 DG182 DG281	P/L	+15 V	10K→GND	—	—	GND	+15 V	+5 V	GND	−15 V	GND	—	—	10K→GND	+15 V				
DG183 DG184 DG185 DG189 DG190 DG191 DG284 DG290	P	10K→GND	—	10K→GND	−15 V	−15 V	10K→GND	—	10K→GND	+15 V	GND	+15 V	+5 V	GND	−15 V	GND	+15 V		

Parentheses indicate direct connection to indicated pin i.e., (2) = connect to pin 2; All voltages  $\pm 5\%$ .

\*Package types: P = All Dual-In-Line Packages, L = All Flat Packages, A = All 10-Lead TO-5s, R = 28 Pin Dual-In-Line Packages.

## Burn-In Pin Connections (Continued)

Part Type	Package Type*	Pins																	
		1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18
DG183 DG184 DG185	L																		
DG186 DG187 DG188	P/L	-15 V	10K - GND	10K - GND	+15 V	GND	+15 V	+5 V	GND	-15 V	GND	+15 V	10K - GND	10K - GND	-15 V				
DG189 DG190 DG191 DG284 DG290	L																		
DG200	A	+15 V	+15 V	GND	(9)	(9)	-15 V	—	(9)	10K - GND	+15 V								
DG200A	P/L	+15 V	—	GND	—	(10)	(10)	-15 V	—	(10)	10K - GND	—	+15 V	—	+15 V				
DG201 DG201A	P/L	+15 V	(15)	(15)	-15 V	GND	(15)	(15)	+15 V	+15 V	(15)	(15)	—	+15 V	(15)	10K - GND	+15 V		
DG211	P	+15 V	(15)	(15)	-15 V	GND	(15)	(15)	+15 V	+15 V	(15)	(15)	+5 V	+15 V	(15)	10K - GND	+15V		
DG300 DG300A DG301 DG301A DG304 DG304A DG305 DG305A	A	(9)	(9)	GND	—	GND	-15 V	GND	(9)	10K - GND	+15 V								
DG300 DG300A DG301 DG301A DG302 DG302A DG303 DG303A DG304 DG304A DG305 DG305A DG306 DG306A DG307 DG307A	P/L	—	(13)	(13)	(13)	(13)	GND	GND	-15 V	GND	(13)	(13)	(13)	10K - GND	+15 V				
DG308 DG308A	P	+15 V	(15)	(15)	-15 V	GND	(15)	(15)	+15 V	+15 V	(15)	(15)	—	+15 V	(15)	10K - GND	+15 V		
DG381 DG381A DG384 DG384A DG387 DG387A DG390 DG390A	A/P A/P A/P A/P	See DG181 See DG184 See DG187 See DG190																	
DG501 DG503 SI3705	P/L	(16)	(4)	(4)	+10 V	(12)	(12)	(12)	(12)	(12)	(12)	(12)	-10 V	-15 V	(16)	(16)	GND		
DG506 DG506A DG507 DG507A	R	1 +15 V 15	2 (28) 16	3 — 17	4 (28) 18	5 (28) 19	6 (28) 20	7 (28) 21	8 (28) 22	9 (28) 23	10 (28) 24	11 (28) 25	12 GND 26	13 — 27	14 GND 28	—	28 Pins		
DG508 DG508A	P/L	GND	GND	-15 V	(12)	(12)	(12)	(12)	(12)	(12)	(12)	(12)	10K - GND	+15 V	GND	GND	GND		
DG509 DG509A	P/L	GND	GND	-15 V	(13)	(13)	(13)	(13)	(13)	(13)	(13)	(13)	10K - GND	+15 V	GND	GND			

Parenteses indicate direct connection to indicated pin i.e., (2) = connect to pin 2; All voltages  $\pm 5\%$ .

\*Package types: P = All Dual-In-Line Packages, L = All Flat Packages, A = All 10-Lead TO-5s, R = 28 Pin Dual-In-Line Packages.

# Burn-In Pin Connections (Continued)

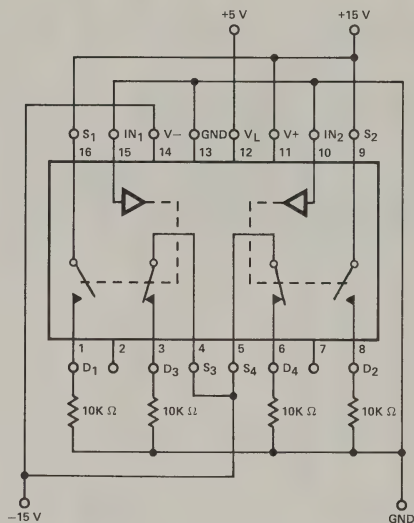
Part Type	Package Type*	Pins																	
		1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18
DG528	P	GND	GND	GND	−15 V	(13)	(13)	(13)	(13)	(13)	(13)	(13)	(13)	10K→ GND	+15 V	GND	GND	GND	GND
DG529	P	GND	GND	GND	−15 V	(14)	(14)	(14)	(14)	(14)	(14)	(14)	(14)	(14)	10K→ GND	+15 V	GND	GND	GND
DG5040 DG5041 DG5042 DG5043 DG5044 DG5045	P	10K→ GND	—	10K→ GND	−15 V	−15 V	10K→ GND	—	10K→ GND	+15 V	GND	+15 V	+5 V	GND	−15 V	GND	+15 V		
DF320	P/J	33Ω to 5V	4.7kΩ to 5V	4.7kΩ to 5V	10kΩ to 5V	(4)	(4)	10kΩ to GND	33kΩ to 5V	4.7kΩ to GND	GND	4.7kΩ to GND	(11)	(11)	(11)	(11)	(11)	(11)	(11)
DF328	P/J	33Ω to 5V	4.7kΩ to 5V	4.7kΩ to 5V	10kΩ to 5V	(4)	10kΩ to GND	33kΩ to 5V	4.7kΩ to GND	GND	4.7kΩ to GND	(10)	(10)	(10)	(10)	(10)	(10)		
G115	P/L	(16)	−15 V	−15 V	−15 V	−15 V	−15 V	−15 V	(16)	(16)	(16)	(16)	(16)	(16)	(16)	(16)	10k→ +10 V		
G116	P/L	(14)	−15 V	−15 V	−15 V	−15 V	−15 V	−15 V	(14)	(14)	(14)	(14)	(14)	(14)	10K→ +10 V				
G118	P/L	−15 V	−15 V	−15 V	−15 V	−15 V	−15 V	(14)	(14)	(14)	(14)	(14)	(14)	(14)	10K→ +10 V				
G119	P/L	(14)	(14)	−15 V	−15 V	−15 V	(14)	(14)	(14)	(14)	(14)	(14)	(14)	(14)	10K→ +10 V				
G122	P/L	(14)	−15 V	−15 V	−15 V	−15 V	−15 V	−15 V	(14)	(14)	(14)	(14)	(14)	(14)	10K→ +10 V				
G123	P/L	(14)	−15 V	−15 V	−15 V	−15 V	−15 V	−15 V	(14)	(14)	(14)	(14)	(14)	(14)	10K→ +10 V				
L144	P/L	3MΩ→ +15 V	(13)	(11)	GND	GND	(9)	—	—	(6)	220→ −15 V	(3)	GND	(2)	→ +15 V				
L161	P	−15 V	+15 V	−15 V	+15 V	−15 V	+15 V	−15 V	+15 V	−15 V	—	—	—	—	—	3MΩ→ +15 V	+15 V		

Parentheses indicate direct connection to indicated pin i.e., (2) = connect to pin 2; All voltages ±5%.

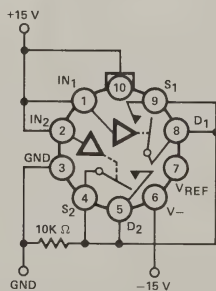
\*Package types: P = All Dual-In-Line Packages, L = All Flat Packages, A = All 10-Lead TO-5s, R = 28 Pin Dual-In-Line Packages.

# Burn-In Pin Connections (Continued)

Examples of Burn-In Circuit Configurations



DG190/DG191 (PACKAGE TYPE P)



DG200 (PACKAGE TYPE A)



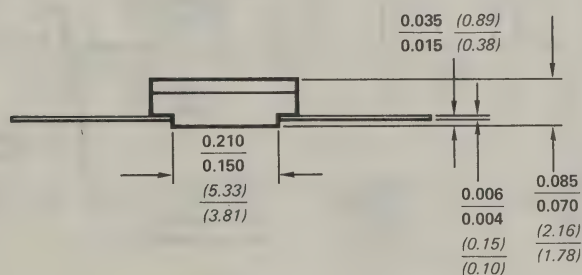
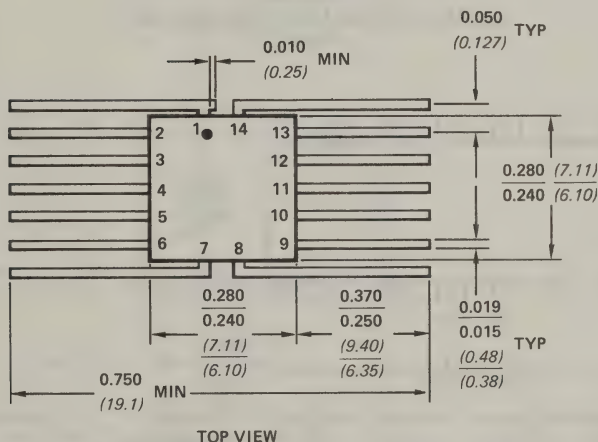
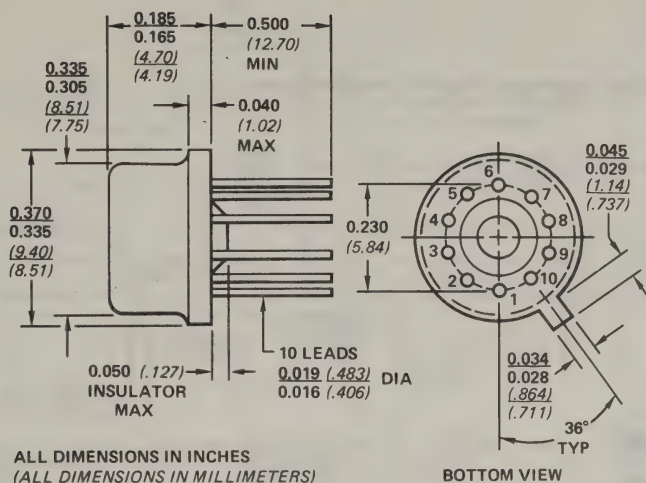


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## PACKAGE DATA

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8	J	16 Pin Plastic Dual-In-Line . . . . .	11-2
9	K	14 Pin Cerdip Dual-In-Line . . . . .	11-3
10	K	16 Pin Cerdip Dual-In-Line . . . . .	11-3
11	P	14 Pin Side-Braze Dual-In-Line . . . . .	11-4
12	P	16 Pin Side-Braze Dual-In-Line . . . . .	11-4
13	R	28 Pin Side-Braze Dual-In-Line . . . . .	11-5
14	J	28 Pin Plastic Dual-In-Line . . . . .	11-5
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22	J	40 Pin Plastic Dual-In-Line . . . . .	11-9
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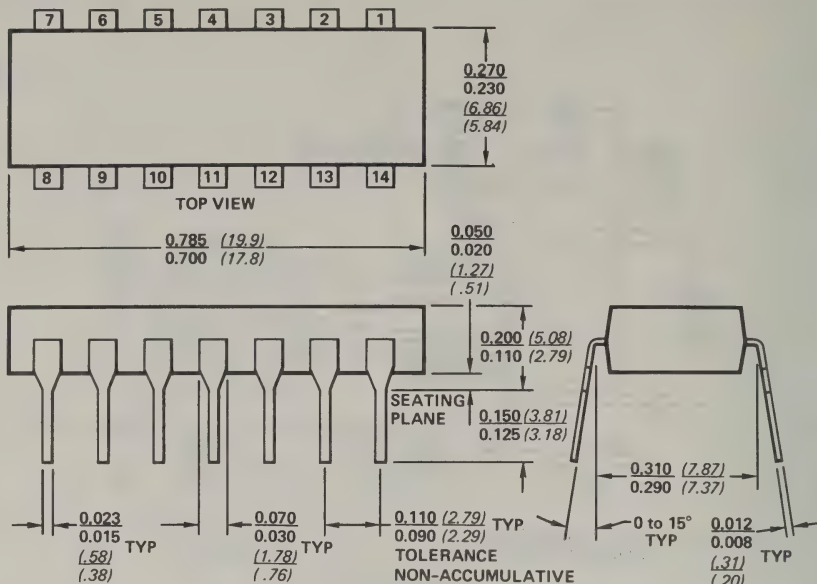


**PACKAGE 5**  
14 LEAD FLATPAC (L)  
(BOTTOM BRAZE)

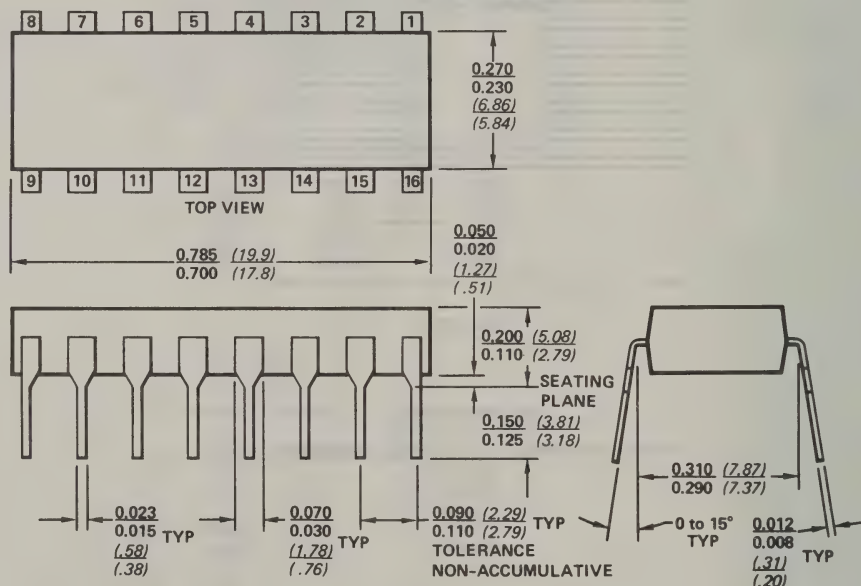
**PIN 1 INDEX IS ONE OR MORE OF THE FOLLOWING**

- DOT (INK OR IMPRESSION) ON TOP AND/OR BOTTOM OF PACKAGE
- NOTCH OR HOLE IN PIN 1 VISIBLE FROM TOP AND/OR SIDE
- NOTCH IN END OF PACKAGE VISIBLE FROM TOP AND/OR BOTTOM

ALL DIMENSIONS IN INCHES  
(ALL DIMENSIONS IN MILLIMETERS)



**PACKAGE 7**  
14 LEAD DUAL IN LINE PACKAGE (J)  
(PLASTIC)



**PACKAGE 8**  
16 LEAD DUAL IN LINE PACKAGE (J)  
(PLASTIC)

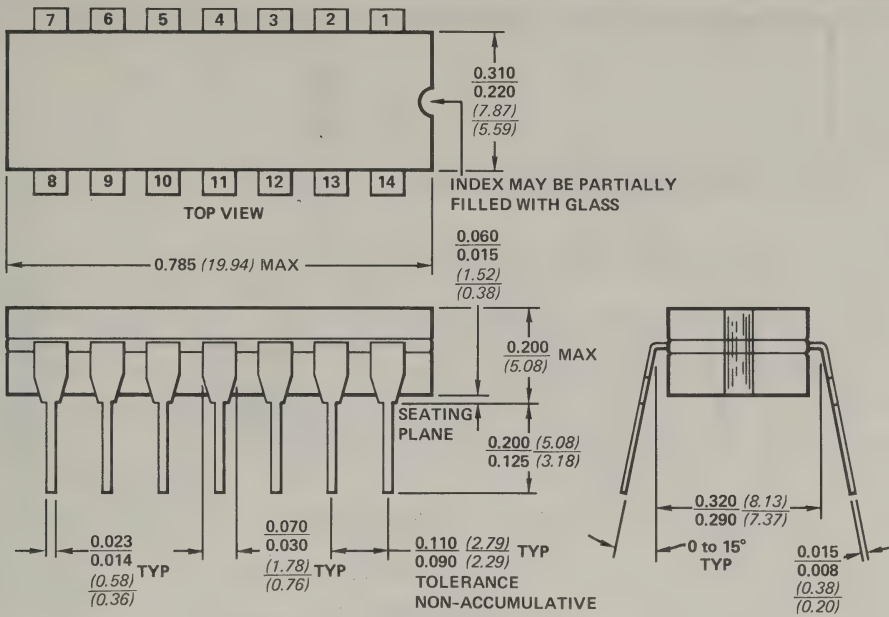
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- DOT (INK OR IMPRESSION) ON TOP OF PACKAGE
- NOTCH OR HOLE IN PIN 1 VISIBLE FROM TOP AND/OR SIDE
- NOTCH IN END OF PACKAGE VISIBLE FROM TOP AND/OR BOTTOM

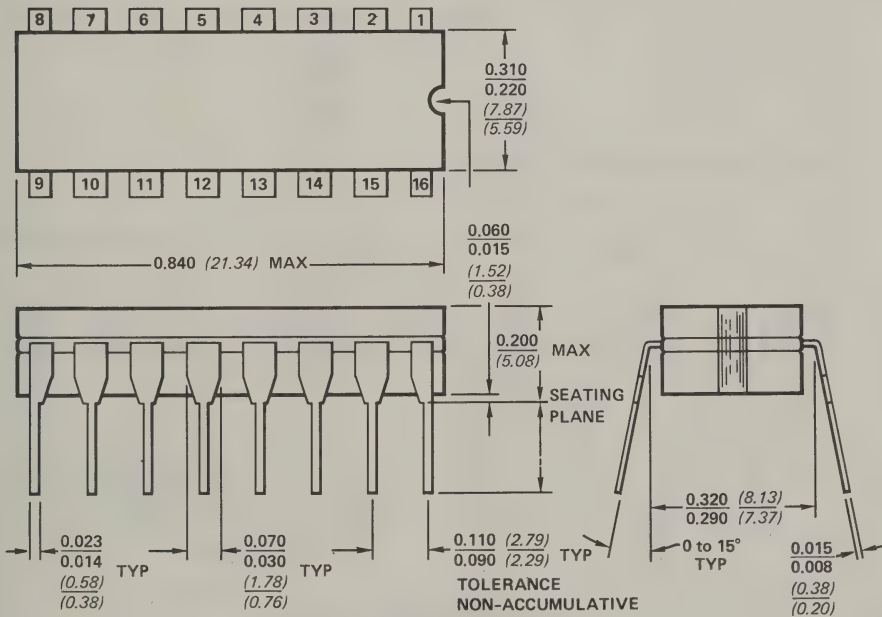
**ALL DIMENSIONS IN INCHES**

**(ALL DIMENSIONS IN MILLIMETERS)**





PACKAGE 9  
14 LEAD DUAL IN LINE PACKAGE (K)  
(CERDIP)

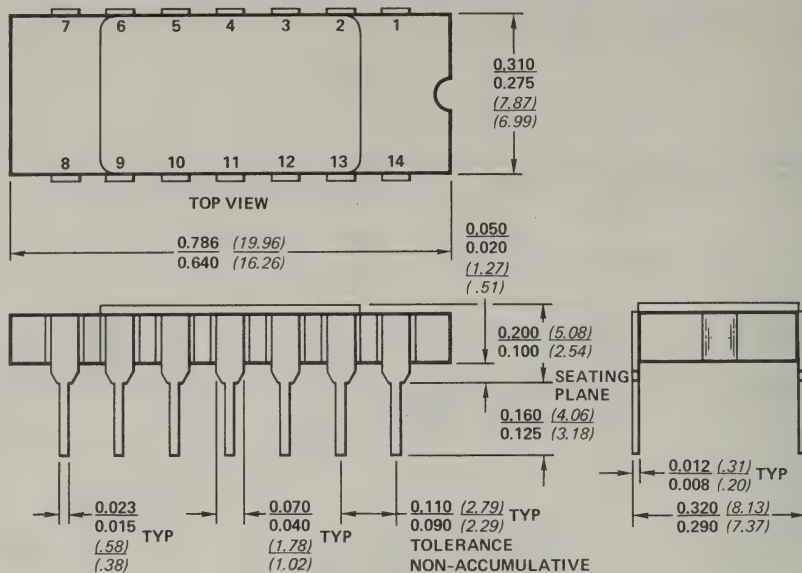


PACKAGE 10  
16 LEAD DUAL IN LINE PACKAGE (K)  
(CERDIP)

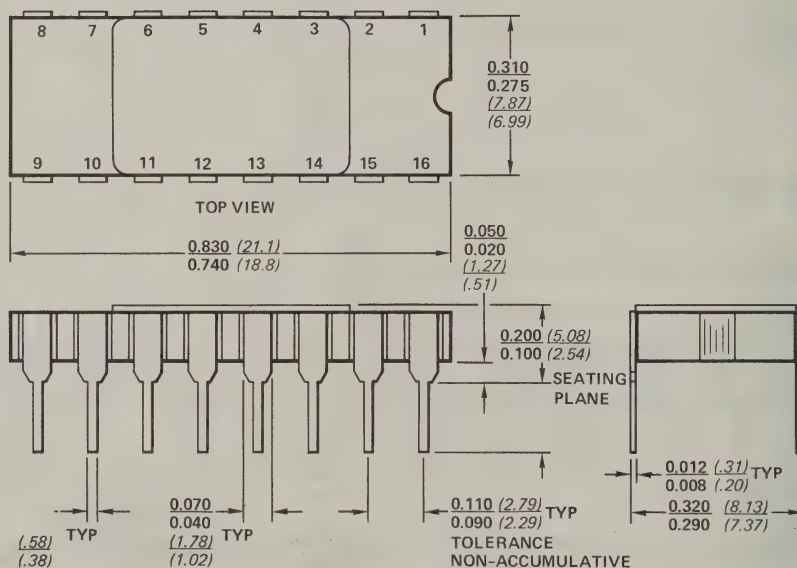
PIN 1 INDEX IS ONE OR MORE OF THE FOLLOWING

- DOT (INK OR IMPRESSION) ON TOP OF PACKAGE
- NOTCH OR HOLE IN PIN 1 VISIBLE FROM TOP AND/OR SIDE
- NOTCH IN END OF PACKAGE VISIBLE FROM TOP AND/OR BOTTOM

ALL DIMENSIONS IN INCHES  
(ALL DIMENSIONS IN MILLIMETERS)



**PACKAGE 11**  
14 LEAD DUAL IN LINE PACKAGE (P)  
(SIDE BRAZE)



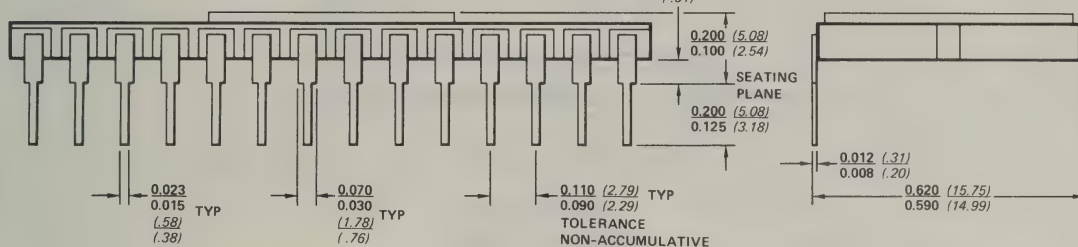
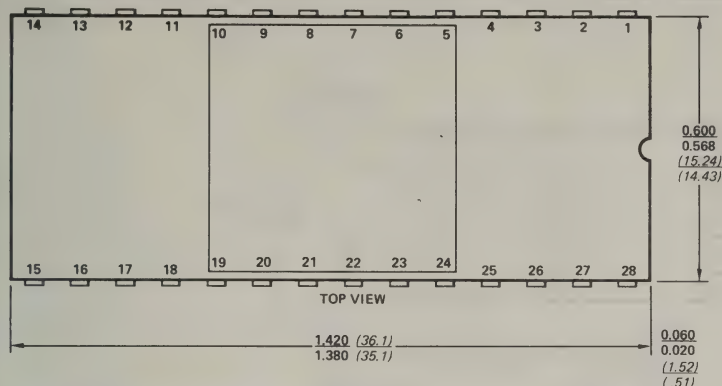
**PACKAGE 12**  
16 LEAD DUAL IN LINE PACKAGE (P)  
(SIDE BRAZE)

PIN 1 INDEX IS ONE OR MORE OF THE FOLLOWING

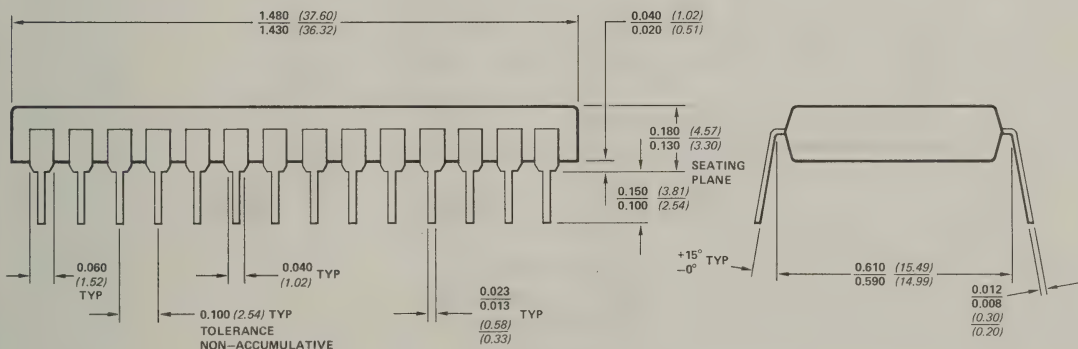
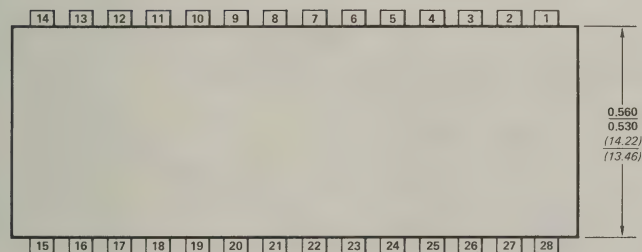
- DOT (INK OR IMPRESSION) ON TOP OF PACKAGE
- NOTCH OR HOLE IN PIN 1 VISIBLE FROM TOP AND/OR SIDE
- NOTCH IN END OF PACKAGE VISIBLE FROM TOP AND/OR BOTTOM

ALL DIMENSIONS IN INCHES

(ALL DIMENSIONS IN MILLIMETERS)



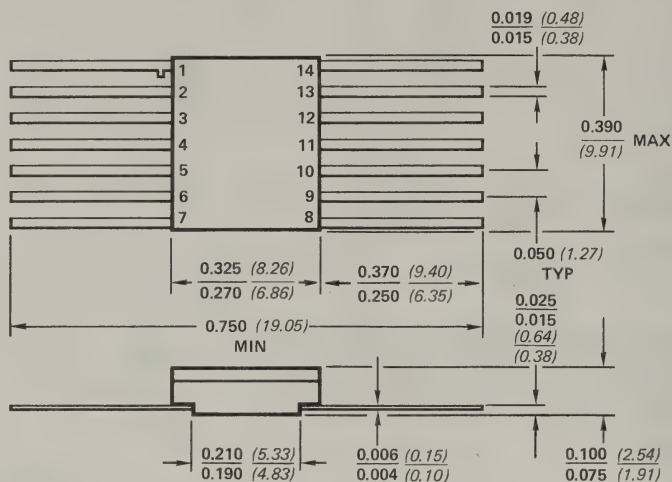
**PACKAGE 13**  
28 LEAD DUAL IN LINE PACKAGE (R)  
(SIDE BRAZE)



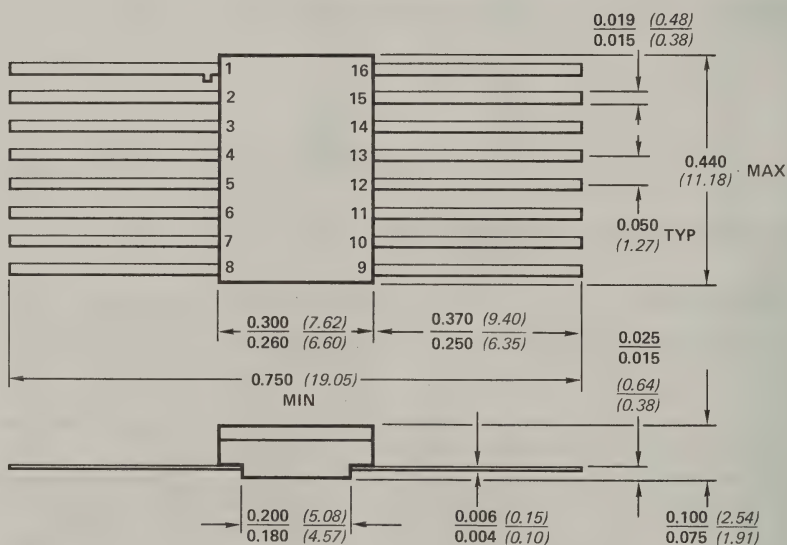
**PACKAGE 14**  
28 LEAD DUAL IN-LINE PACKAGE (J)  
(PLASTIC)

**PIN 1 INDEX IS ONE OR MORE OF THE FOLLOWING**

- DOT (INK OR IMPRESSION) ON TOP AND/OR BOTTOM OF PACKAGE
- NOTCH OR HOLE IN PIN 1 VISIBLE FROM TOP AND/OR SIDE
- NOTCH IN END OF PACKAGE VISIBLE FROM TOP AND/OR BOTTOM



**PACKAGE 16**  
14 LEAD FLATPAC (L)  
(BOTTOM BRAZE)



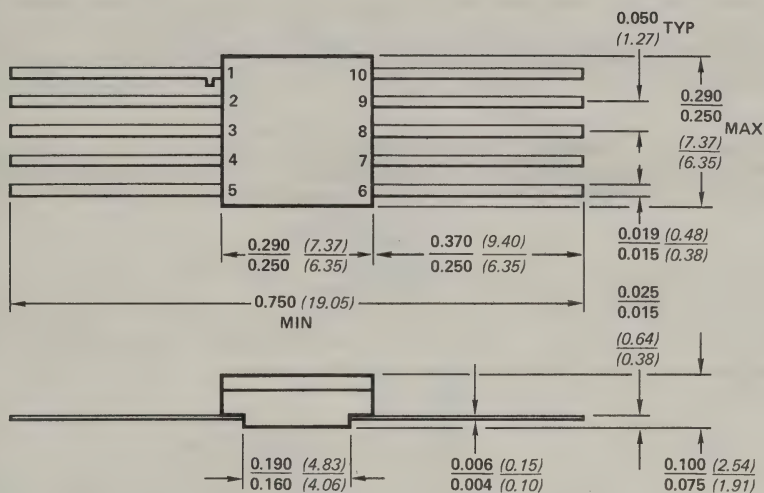
**PACKAGE 17**  
16 LEAD FLATPAC (L)  
(BOTTOM BRAZE)

**PIN 1 INDEX IS ONE OR MORE OF THE FOLLOWING**

- DOT (INK OR IMPRESSION) ON TOP AND/OR BOTTOM OF PACKAGE
- NOTCH OR HOLE IN PIN 1 VISIBLE FROM TOP AND/OR SIDE
- NOTCH IN END OF PACKAGE VISIBLE FROM TOP AND/OR BOTTOM

ALL DIMENSIONS IN INCHES  
(ALL DIMENSIONS IN MILLIMETERS)



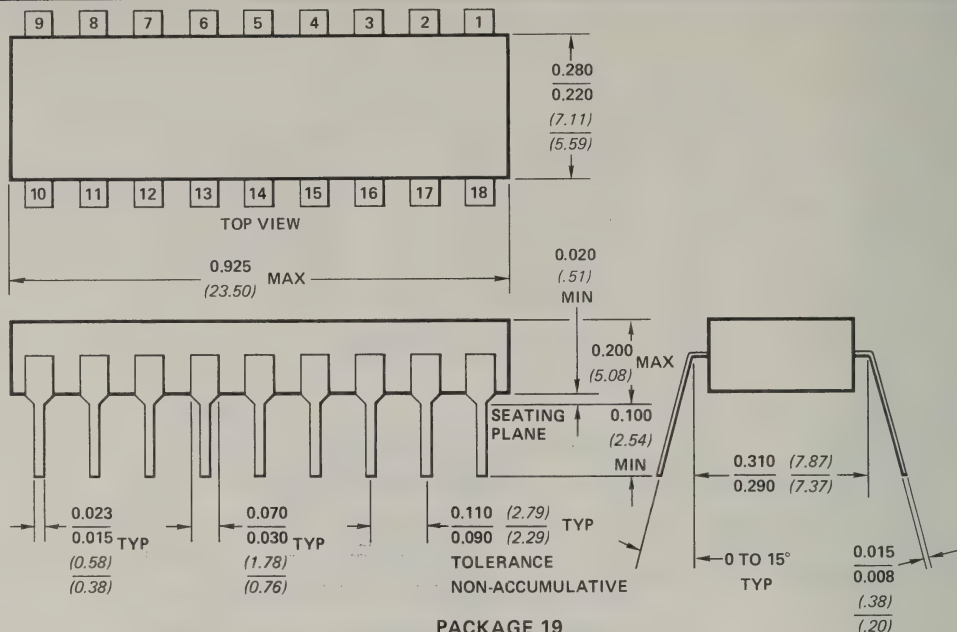


**PACKAGE 18**  
**10 LEAD FLATPAC (L)**  
**(BOTTOM BRAZE)**

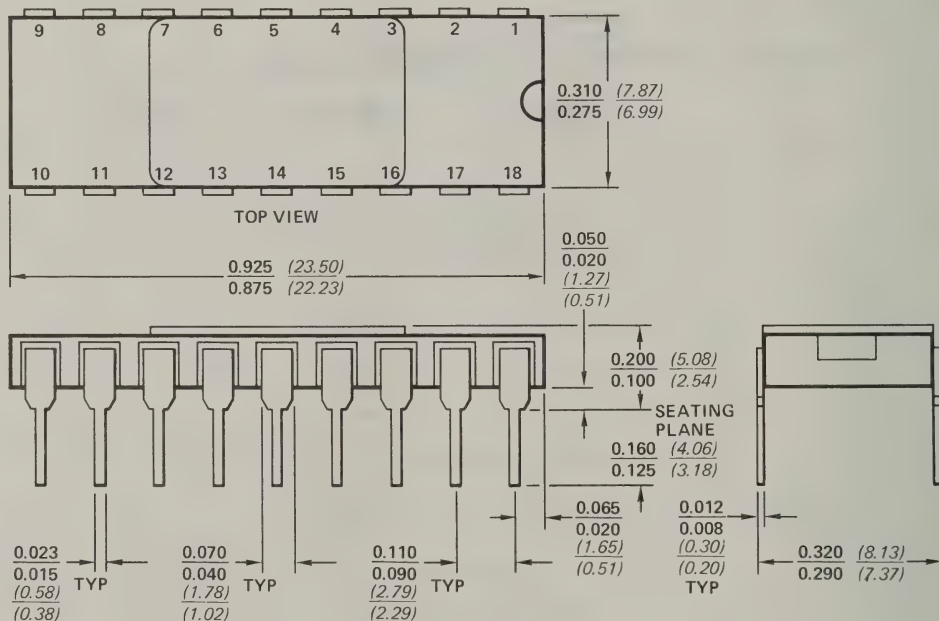
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- DOT (INK OR IMPRESSION) ON TOP AND/OR BOTTOM OF PACKAGE
- NOTCH OR HOLE IN PIN 1 VISIBLE FROM TOP AND/OR SIDE
- NOTCH IN END OF PACKAGE VISIBLE FROM TOP AND/OR BOTTOM

**ALL DIMENSIONS IN INCHES**  
**(ALL DIMENSIONS IN MILLIMETERS)**



**PACKAGE 19**  
**18 LEAD DUAL IN-LINE PACKAGE (J)**  
**(PLASTIC)**



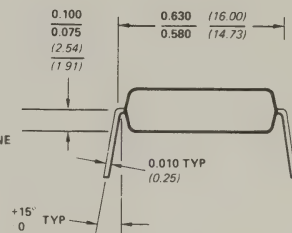
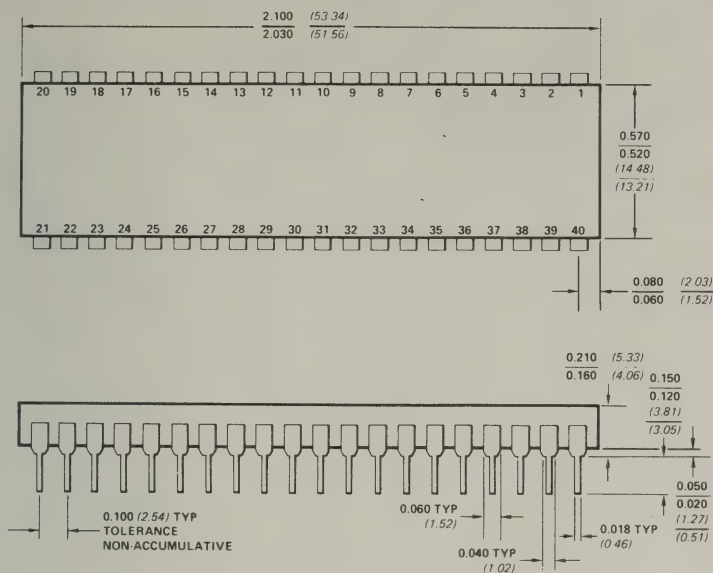
**PACKAGE 20**  
**18 LEAD DUAL IN-LINE PACKAGE (P)**  
**(SIZE BRAZE)**

**PIN 1 INDEX IS ONE OR MORE OF THE FOLLOWING**

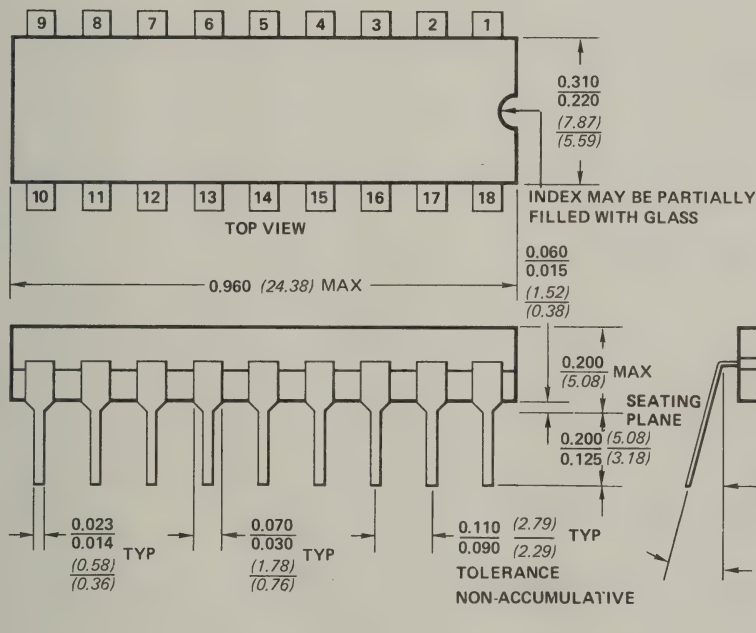
- DOT (INK OR IMPRESSION) ON TOP AND/OR BOTTOM OF PACKAGE
- NOTCH OR HOLE IN PIN 1 VISIBLE FROM TOP AND/OR SIDE
- NOTCH IN END OF PACKAGE VISIBLE FROM TOP AND/OR BOTTOM

**ALL DIMENSIONS IN INCHES**

**(ALL DIMENSIONS IN MILLIMETERS)**



**PACKAGE 22**  
**40 LEAD DUAL IN-LINE PACKAGE (J)**  
**(PLASTIC)**



**PACKAGE 23**  
**18 LEAD DUAL IN-LINE PACKAGE (K)**  
**(CERDIP)**

**PIN 1 INDEX IS ONE OR MORE OF THE FOLLOWING**

- DOT (INK OR IMPRESSION) ON TOP AND/OR BOTTOM OF PACKAGE
- NOTCH OR HOLE IN PIN 1 VISIBLE FROM TOP AND/OR SIDE
- NOTCH IN END OF PACKAGE VISIBLE FROM TOP AND/OR BOTTOM

ALL DIMENSIONS IN INCHES  
(ALL DIMENSIONS IN MILLIMETERS)





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## APPENDICES

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# Publications Index

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<b>Application Notes</b>					
	AN70-1	FET Cascode Circuits Reduce Feedback Capacitance	VA	* AN80-1	A Key to the Advance of Switching Power Supplies
F	AN70-2	FETs for Video Amplifiers	VA	AN80-2	Meet the VMOS FET Model
	AN71-1	A High Resolution CMRR Test Method		AN80-3	Ultralinear Broadband Amplifier
F	AN72-1	FETs in Balanced Mixers		AN80-4	Enjoy VHF Power Amplifier Design
A	AN72-2	FETs as Analog Switches	VA	* AN80-5	An Alternative Power Amplifier Design
F	AN73-1	FETs as Voltage-Controlled Resistors		AN80-6	AGC for the VMOS RF Power Amplifier
A	AN73-2	IC Multiplexer Increases Analog Switching Speeds	AIC	AN80-8	Function/Application of the LD122/LD121A $\pm 4\frac{1}{2}$ Digit A/D Converter Set in Measurement Systems
A	AN73-3	Switching High-Frequency Signals With FET Integrated Circuits			
	AN73-4	Junction FETs in Active Double-Balanced Mixers	AIC	AN81-1	Microprocessor Interface Techniques As Applied to the Siliconix A/D Converter Family
A	* AN73-5	Driver Circuits for the JFET Analog Switch	AIC	AN81-2	Introduction to Quantized Feedback
AIC	AN73-6	Function/Application of the L144 Programmable Micro-Power Triple Op Amp	F	* AN81-3	Composite Op Amp for High Performance
F, A	* AN73-7	An Introduction to FETs	<b>Design Aids</b>		
AIC	* AN74-1	Function/Application of the LD110/LD111 $3\frac{1}{2}$ Digit A/D Converter Set	AIC	* DA77-2	Design Aid of the LD120/LD121 $4\frac{1}{2}$ Digit DVM
A	AN74-2	Analog Switches in Sample and Hold Circuits		DA78-4	Build a Smoke Detector With the SM110 IC
	AN74-3	Designing Junction FET Input Op Amps	VA	* DA80-1	A Low Cost Regulator for Microprocessor Applications
F	* AN74-4	Audio-Frequency Noise Characteristics of Junction FETs		DA81-1	Logic Interfacing Made Easy with the DG308
A	* AN75-1	CMOS Analog Switches—A Powerful Design Tool		DA81-2	Logic Interfacing Made Easy with the DG308
	AN76-1	Measuring High Frequency S-Parameters on the Dual Gate MOSFET	<b>Design Ideas</b>		
VA	* AN76-3	VMOS—A Breakthrough in Power MOSFET Technology	F	* DI71-1	The FET Constant Current Source
A	* AN76-6	DG300 Series Analog Switch Applications		DI71-4	Wideband Mixer-Preamplifier Using FETs
AIC	* AN76-7	Function/Application of the L161 Micropower Comparator		DI71-5	A FET Frequency Doubler
AIC	* AN77-1	Function/Application of the LD120/LD121 $4\frac{1}{2}$ Digit A/D Converter Set in Measurement Systems		DI71-6	Using FETs in Selective VHF Amplifiers
				DI71-8	Using JFETs in Ultra-Wideband UHF Amplifiers
VA	* AN77-2	Don't Trade Off Analog Switch Specs. VMOS—A Solution to High Speed, High Current, Low Resistance Analog Switches	F	DI71-9	Wideband UHF Amplifier with High Performance FETs
			F	* DI73-2	High Performance FETs in Low-Noise VHF Oscillators
				DI80-1	A 5 Watt, Parallel-Mode Crystal Oscillator
VA	* AN79-1	A 500 KHz Switching Inverter for 12 V Systems			
VA	* AN79-3	Dynamic Input Characteristics of a VMOS Power Switch		TA70-1	High Frequency Junction FET Characterization and Application
VA	* AN79-4	Driving VMOS Power FETs	F	* TA70-2	FET Biasing
	AN79-5	Using the VN64GA High Current, High Power VMOS Power FET	A	* TA73-1	Multiplexer Adds Efficiency to 32-Channel Telephone System
VA	* AN79-6	Using VMOS Transistors to Interface from IC Logic to High Power Loads	A	TA73-2	Designing with Monolithic FET Switches
	AN79-7	Applications of the VN10KM VMOS Power FET		TA76-1	VMOS Power FETs in Your Next Broadband Driver

# Publications Index (Cont'd)

Catalog (See Key)	Document Number	Title
	TA76-2	A New Technology: Application of VMOS Power FETs for High Frequency Communications
VA	* TA78-2	Designing a VMOS 250 Watt Off-Line Inverter

## Catalogs

Analog Switch & IC Product Data Book  
 Analog Switches and Their Applications (\$7.95 charge)  
 FET Design Catalog  
 VMOS Power FETs Design Catalog  
 VMOS Power FETs Applications Handbook  
 OEM Pricing with Cross Reference  
 RF Power FET Short Form Catalog  
 Siliconix Short Form Selector Guide

## Key

### Catalogs

AIC = Analog Switch & IC Product Data Book  
 A = Analog Switches and Their Applications  
 F = FET Design Catalog  
 VA = VMOS Applications Handbook

\* Available in bound catalog only.

## Title

### Reprints & Reports

- Siliconix, Inc. Annual Report.
- Designing a VMOS 250 Watt Off-Line Inverter. David C. Hoffman, *Powercon* 3/78
- Designing with CODECs: Know Your A's and  $\mu$ 's. Thomas J. Mroz, *EDN* 5/76
- Log Data under  $\mu$  Control. Gary Grandbois, *Electronic Design* 5/76
- Higher Power Ratings Extend VMOS FETs' Dominion. Arthur D. Evans, David C. Hoffman, Edwin S. Oxner, Walter Heinzer and Lee Shaeffer. *Electronics* 6/78
- CODEC has On-Chip Signaling for Phone Applications. Walter Heinzer and Steve Bolger, *Electronics* 6/7/79
- A Microprocessor Controlled VMOS Power Supply. David C. Hoffman
- Control Analog Signals with Voltage. Stephen Moore, *Electronic Design*, 1978
- Exploit VMOS FETs' Advantages to Drive Bipolar Power Transistors. F. Michael Barlage, *Powercon* 5/78
- Rely on IC Analog Switches for Fast Small-Signal Control, *EDN*, August 5, 20, Sept. 5, 1980
- Composite Op Amp Outperforms FET-input ICs, *EDN*, May 27, 1981.

### Book

*Designing with Field-Effect Transistors*, Edited by Arthur D. Evans. Available at your technical bookstore or write to Suite 26-1; McGraw Hill Book Co.; 1221 Avenue of the Americas; New York, NY 10020.



# Glossary of Terms and Abbreviations

$A_V$	— DC Closed Loop Voltage Gain	$I_{OL}$	— Output Current, Output Voltage Low
$A_{VOL}$	— DC Open Loop Voltage Gain	$I_{OS}$	— Input Offset Current
AZ IN	— Auto-Zero Amplifier Input	$I_R$	— Reference Supply Current
AZ OUT	— Auto-Zero Amplifier Output	$I_{RH}$	— Reference Supply Current, Input Voltage High
BCD	— Binary Coded Decimal	$I_{RL}$	— Reference Supply Current, Input Voltage Low
$B_n$	— BCD Data Bit Outputs	$I_S$	— Supply Current or FET Source Current
$C_{AZ}$	— Auto-Zero Storage Capacitance	$I_{SC}$	— Output Short Circuit Current
$C_{INT}$	— Integrator Capacitance	$I_{S(off)}$	— Source OFF Leakage Current
$C_L$	— Load Capacitance	$I_{SS}$	— Source Supply Current
CMR	— Common Mode Range	$I_1$	— Positive Supply Current
CMRR	— Common Mode Rejection Ratio	$I_2$	— Negative Supply Current
COMP	— Analog Comparator Output	$I_+$	— Positive Supply Current
$C_{OSC}$	— Oscillator Capacitance	$I_-$	— Negative Supply Current
$C_{STRG}$	— Auto-Zero Storage Capacitance	LSB	— Least Significant Bit
$D_n$	— Digit Strobe Outputs	MSB	— Most Significant Bit
EOC	— End of Conversion Signal	M/Z	— Measure-Zero Logic Output
$f_{CLK}$	— Clock Frequency	NC	— No Connection
$f_{IN}$	— Clock Input Frequency	NMR	— Normal Mode Rejection at Input
$f_L$	— Line Frequency	OC	— Open Collector Logic
$f_o$	— Resonant Frequency	OF	— Overflow Logic Output Pulse
FS	— Full Scale	OR	— Overrange Logic Output Pulse
$H_o$	— Gain at the Resonant Frequency	P	— Pull-Up Gate
$I_{BIAS}$	— Input Bias Current	$P_D$	— Power Dissipation
$I_{CL}$	— Clock Input Current, Clock Voltage Low	P-P	— Peak to Peak
$I_{DD}$	— Drain Supply Current	PSRR	— Power Supply Rejection Rate
$I_{IN}$	— Input Current	Q	— Quality Factory
$I_{INH}$	— Logic Input Current, Input Voltage High	$r_{DS(on)}$	— ON Resistance of FET Switch
$I_{INL}$	— Logic Input Current, Input Voltage Low		— Drain-Source ON Resistance (D.C. measurement)
INT IN	— Integrator Summing Node (Input)	REF <sub>out</sub>	— Reference Output Voltage
INT OUT	— Integrator Amplifier Output	$R_{in}$	— Input Resistance
$I_o$	— Output Current		
$I_{OH}$	— Output Current, Output Voltage High		

# Glossary of Terms and Abbreviations (Cont'd)

$R_L$	— Load Resistance	$V_{GD}$	— Gate-Drain Voltage
$R_S$	— Input Source Resistance	$V_{GS}$	— Gate-Source Voltage
$R_{SET}$	— Set Current Resistance	$V_{GS(off)}$	— Gate-Source Pinchoff Voltage
$S$	— Source	$V_{GS(th)}$	— Gate-Source Threshold Voltage
SCAN	— Sequential/Interlace Digit Scan Logic Input	$V_{HI-Q}$	— High Quality Ground Input Voltage
$S_R$	— Slew Rate	$V_{IN}$	— Input Voltage
$T_A$	— Ambient Temperature	$V_{INH}$	— Logic Input Voltage, High
TC	— Temperature Coefficient	$V_{INL}$	— Logic Input Voltage, Low
$t_{off}$	— Turn-Off Time	$V_L$	— Logic Supply Voltage
$t_{off(En)}$	— Enable Turn-Off Time	$V_O$	— Output Voltage
$t_{on}$	— Turn-On Time	$V_{OH}$	— Output Voltage, High
$t_{on(En)}$	— Enable Turn-On Time	$V_{OL}$	— Output Voltage, Low
$t_{open}$	— Break-Before-Make Interval	$V_{OS}$	— Input Offset Voltage
$t_r$	— Response Time	$V_{OUT}$	— Output Voltage Swing
$t_{transition}$	— Switching Time of Multiplexer	$V_P$	— Pull-Up Gate Voltage
U/D	— Up/Down Logic Output	$V_{PB}$	— Pull-Up Gate to Body Voltage
UR	— Underrange Logic Output Pulse	$V_R$	— Reference Voltage
$V_A$	— Address Input Voltage	$V_{REF}$	— Threshold Reference Voltage
$V_{AH}$	— Address Input Voltage, High		— Positive Reference Voltage
$V_{AL}$	— Address Input Voltage, Low	$V_S$	— Source Supply Voltage
$V_{AZ}$	— Auto-Zero Amplifier Output Voltage	$V_{SB}$	— Source-Body Voltage
$V_{AZ(in)}$	— Auto-Zero Switch Input Voltage	$V_{SS}$	— Source Supply Voltage; Positive for PMOS, Negative for NMOS and CMOS
$V_B$	— Body Voltage	$V_{STRG}$	— Auto-Zero Loop Storage Voltage
$V_{CLOCK IN}$	— Clock Logic Input Voltage	$V_1$	— Positive Supply Voltage
$V_D$	— Drain Voltage	$V_2$	— Negative Supply voltage
$V_{DB}$	— Drain-Body Voltage	$V_+$	— Positive Supply Voltage
$V_{DD}$	— Drain Supply Voltage; Negative for PMOS, Positive for NMOS and CMOS	$V_-$	— Negative Supply Voltage
$V_{En}$	— Enable Input Voltage	$Z_{IN}$	— Input Impedance
$V_G$	— Gate Voltage	$\Delta r_{DS(on)}$	— Fractional Change in Drain-Source ON Resistance (D.C. measurement)
$V_{GB}$	— Gate-Body Voltage		

# U.S. Sales Offices

## Eastern

**Siliconix Incorporated**  
31 Bailey Avenue  
Ridgefield, CT 06877  
(203) 431-3535

**Siliconix Incorporated**  
395 Totten Pond Rd.  
Waltham, MA 02154  
(617) 890-7180  
Twx: 710-324-1783

## Central

**Siliconix Incorporated**  
1327 Butterfield Rd., Suite 620  
Downers Grove, IL 60515  
(312) 960-0106/07/08  
Twx: 910-695-3232

**Siliconix Incorporated**  
Two King James South, Suite 143  
24650 Center Ridge Road  
Westlake, OH 44145  
(216) 835-4470

**Siliconix Incorporated**  
P.O. Box 487  
(403 E. Wall)  
Grapevine, TX 76051  
(817) 481-5815/6

## Northwestern

**Siliconix Incorporated**  
2201 Laurelwood Rd.  
Santa Clara, CA 95054  
(408) 988-8000  
Twx: 910-338-0227

## Southwestern

**Siliconix Incorporated**  
1525 E. 17th St., Suite L  
Santa Ana, CA 92701  
(714) 547-4474  
Twx: 910-595-2643

# U.S. Sales Representatives

**ALABAMA, Huntsville (35803)**  
Rep. Inc.  
11527 S. Memorial Pkwy.  
(205) 881-9270  
Twx: 810-726-2102

**ARIZONA, Tempe (85281)**  
Quatra Associates, Inc.  
1801 S. Jen Tilly  
Suite C-14  
(602) 894-2808  
Twx: 910-950-1153

**CALIFORNIA, Cupertino (95014)**  
Costar Incorporated  
10080 North Wolfe Rd., Suite SW3-175  
(408) 446-9339  
Twx: 910-338-0206

**CALIFORNIA, Fountain Valley (92708)**  
Bager Electronics Inc.  
17220 Newhope St., #211  
(714) 957-3367  
(213) 433-1687

**COLORADO, Englewood (80112)**  
Delta Sales Assoc.  
Bldg. 8 — Penthouse F  
14 Inverness Dr. E.  
(303) 741-0646  
Twx: 910-935-0717

**CONNECTICUT, Ridgefield (06877)**  
Phoenix Sales Company  
389 Main Street  
(203) 438-9644  
Twx: 710-467-0662

**FLORIDA, Largo (33540)**  
Perrott Associates  
511 Rosery Rd. NE  
(813) 585-3327  
Twx: 810-866-0328

**FLORIDA, Orlando (32807)**  
Perrott Associates  
1607 Forsyth Road  
(305) 275-1132  
Twx: 810-850-0103

**FLORIDA, Sunrise (33313)**  
Perrott Associates  
5975 W. Sunrise Blvd., Suite 212  
(305) 792-2211  
Twx: 510-955-9831

**GEORGIA, Norcross (30692)**  
Montgomery Marketing  
3640 Peachtree Corner W., #303  
(404) 447-6124

**ILLINOIS, Des Plaines (60018)**  
Electron Marketing Corp.  
3166 Des Plaines Ave.  
Suite 35  
(312) 298-2330

**INDIANA, Carmel (46032)**  
Wilson Technical Sales Inc.  
597 Industrial Drive  
(317) 844-5977

**IOWA, Cedar Rapids (52402)**  
Technical Reps Inc.  
1930 St. Andrews Dr. N.E.  
(319) 393-1300  
Twx: 910-525-1351

**KANSAS, Wichita (67206)**  
Technical Reps Inc.  
360 No. Rock Rd., #4  
(316) 681-0242

**MARYLAND, Baltimore (21208)**  
Pro Rep  
107 Sudbrook Lane  
(301) 653-3600  
Twx: 710-862-0862

**MASSACHUSETTS, Reading (01867)**  
Kanan Associates  
270 Main Street  
(617) 944-8484  
Twx: 710-393-6552

**MICHIGAN, Brighton (48116)**  
A.P.J. Associates  
P.O. Box 777  
9880 E. Grand River Ave.  
(313) 229-6550  
Twx: 510-242-1510

**MINNESOTA, Burnsville (55337)**  
Electromec Sales Inc.  
101 W. Burnsville Pkwy.  
(612) 894-8200  
Twx: 910-576-0232

**MISSOURI, Earth City (63045)**  
Technical Reps Inc.  
502 Earth City Plaza, #201  
(314) 291-0001  
Twx: 910-762-0685

**MISSOURI, Kansas City (64111)**  
Technical Reps Inc.  
406 W. 34th, #616 VFW Bldg.  
(816) 756-3575  
Twx: 910-749-6412

**NEBRASKA, Lincoln (68507)**  
Technical Reps Inc.  
2332 No. Cotner, Suite D-12  
(402) 466-3488

**NEW JERSEY, Marlton (08053)**  
B.G.R. Associates  
3001 Greentree Exec. Campus  
(609) 428-2440  
Twx: 510-665-5685

**NEW JERSEY, Teaneck (07666)**  
R.T. Reid Associates  
705 Cedar Lane  
(201) 692-0200  
Twx: 710-990-5086

**NEW YORK, Endwell (13760)**  
Tri-Tech Electronics  
3215 E. Main St.  
(607) 754-1094  
Twx: 510-252-0891

**NEW YORK, Fairport (14450)**  
Tri-Tech Electronics  
590 Perinton Hills Office Park  
(716) 223-5720  
Twx: 510-253-6356

**NEW YORK, Fayetteville (13066)**  
Tri-Tech Electronics  
6836 E. Genesee St.  
(315) 446-2881  
Twx: 710-541-0604

**NEW YORK, Poughkeepsie (12603)**  
Tri-Tech Electronics  
19 Davis Ave.  
(914) 473-3880

**NORTH CAROLINA, Cary (27511)**  
Montgomery Marketing  
P.O. B. 520 (1391 N. Harrison Ave.)  
(919) 467-6319  
Twx: 510-920-0634

**OHIO, Cleveland (44143)**  
Arthur H. Baier Company  
67 Alpha Park  
(216) 461-6161  
Twx: 810-427-9278

**OHIO, Dayton (45414)**  
Arthur H. Baier Company  
4940 Profit Way  
(513) 276-4128

**OREGON, Beaverton (97005)**  
Blair Hirsh Co., Inc.  
9645 S.W. Beaverton Hwy.  
(503) 641-1875

**TENNESSEE, Jefferson City (37760)**  
Rep Inc.  
P.O. B. 287 (113 So. Branner Ave.)  
(615) 475-4105  
Twx: 810-570-4203

**TEXAS, Austin (78753)**  
Electronics Marketing Assoc.  
607A Deen Avenue  
(512) 837-0893

**TEXAS, Grapevine (76051)**  
Electronics Marketing Assoc.  
P.O. Box 487  
(403 E. Wall)  
(817) 481-7502 or 7503

**TEXAS, Houston (77042)**  
Electronics Marketing Assoc.  
P.O. Box 42388  
11450 Dissonnet, #309  
(713) 498-8120

**VIRGINIA, Charlottesville (22901)**  
Pro Rep  
1616 Inglewood Dr.  
(804) 997-0031  
Twx: 710-236-9011

**WASHINGTON, Seattle (98107)**  
Blair Hirsh Co., Inc.  
4013 Leary Way NW  
(206) 783-3423

**WISCONSIN, Milwaukee (53227)**  
JM Sales  
9431 W. Beloit Rd., #119  
(414) 546-0040  
Twx: 910-651-5777

## CANADA

**ONTARIO, Etobicoke (M9C 1E7)**  
R.F.Q. Ltd.  
385 The West Mall, Suite 251  
(416) 626-1445  
Twx: 610-492-2540

**ONTARIO, Ottawa (K2B 7E9)**  
R.F.Q. Ltd.  
2249 Carling Ave., #204  
(613) 820-8445 or 820-8446

## U.S. CHIP DISTRIBUTORS

**FLORIDA, Orlando (32807)**  
Chip Supply Inc.  
1607 Forsyth Road  
(305) 275-3810  
Twx: 810-850-0103

**PENNSYLVANIA, Malvern (19335)**  
Hybrid Die Technology  
111 Great Valley Pkwy.  
(215) 296-5905  
Twx: 510-668-6123



# U.S. Distributors

**ALABAMA, Huntsville (35805)**  
Hamilton/Avnet  
4692 Commercial Drive  
(205)837-7210  
Twx: 810-726-2162

**ALABAMA, Huntsville (35805)**  
Pioneer/Huntsville  
1207 Putnam Dr. NW  
(205)837-9300  
Twx: 810-726-2197

**ARIZONA, Scottsdale (85253)**  
Components Plus  
7500 E. Butherus, Ste. T  
(602)991-6510  
Twx: 910-950-1184

**ARIZONA, Tempe (85281)**  
Hamilton/Avnet  
505 South Madison Dr.  
(602)894-9600  
Twx: 910-950-0077

**CALIFORNIA, Costa Mesa (92626)**  
Avnet Elec.  
350 McCormick Ave.  
(714)754-6111  
Twx: 910-595-1928

**CALIFORNIA, Costa Mesa (92626)**  
Hamilton Electro Sales  
3170 Pullman St.  
(714)641-4100  
Twx: 910-595-2638

**CALIFORNIA, Culver City (90230)**  
Hamilton Electro Sales  
10912 W. Washington Bl.  
(213)558-2121 or (714)522-8200  
Twx: 910-340-6364

**CALIFORNIA, Irvine (92714)**  
Components Plus  
17811 Skypark Circle  
(714)754-0471  
Twx: 910-595-2554

**CALIFORNIA, San Diego (92121)**  
Anthem Electronics, Inc.  
4125 Sorrento Valley Blvd.  
(714)453-9005  
Twx: 910-335-1515

**CALIFORNIA, San Diego (92123)**  
Hamilton/Avnet  
4545 Viewridge Ave.  
(714)571-5710  
Twx: 910-335-1216

**CALIFORNIA, Santa Clara (95052)**  
Wyle Distribution Group  
3000 Bowers Ave.  
(408)727-2500  
Twx: 910-379-6480

**CALIFORNIA, Sunnyvale (94086)**  
Bell Industries  
1161 No. Fair Oaks Ave.  
(408)734-8570  
Twx: 910-339-9378

**CALIFORNIA, Sunnyvale (94086)**  
Components Plus  
491 Macara Ave., Ste. 1006  
(408)732-0990

**CALIFORNIA, Sunnyvale (94086)**  
Hamilton/Avnet  
1175 Bordeaux  
(408)743-3355  
Twx: 910-339-9332

**CALIFORNIA, Tustin (92680)**  
Anthem Electronics, Inc.  
2661 Dow Ave.  
(714)730-8000  
Twx: 910-595-1585

**COLORADO, Englewood (80111)**  
Hamilton/Avnet  
8765 E. Orchard Rd., Suite 708  
(303)740-1000  
Twx: 910-931-0510

**COLORADO, Thornton (80241)**  
Wyle Distribution Group  
451 E. 124th Ave.  
(303)457-9953  
Twx: 910-936-0770

**COLORADO, Wheatridge (80033)**  
Bell Industries  
8155 W. 48th Ave.  
(303)424-1985  
Twx: 910-938-0393

**CONNECTICUT, Danbury (06810)**  
Hamilton/Avnet  
Commerce Drive, Commerce Park  
(203)797-2800  
Twx: 710-460-0594

**CONNECTICUT, Wallingford (06492)**  
Marshall Industries  
Village Lane  
Barnes Industrial Park  
(203)265-3822  
Twx: 710-465-0747

**FLORIDA, Ft. Lauderdale (33309)**  
Hamilton/Avnet  
6801 N.W. 15th Way  
(305)971-2900  
Twx: 510-995-3097

**FLORIDA, Orlando (32809)**  
Pioneer Elec.  
6220 S. Orange Blossom Trail, Ste. 412  
(305)859-3600  
Twx: 810-850-0177

**FLORIDA, St. Petersburg (33702)**  
Hamilton/Avnet  
3197 Tech Drive No.  
(813)576-3930  
Twx: 810-863-0374

**GEORGIA, Norcross (30092)**  
Hamilton/Avnet  
5825 Peachtree Corners E-D  
(404)447-7500  
Twx: 810-766-0432

**GEORGIA, Norcross (30093)**  
Marshall Industries  
4364B Shakelford Rd.  
(404)923-5750

**ILLINOIS, Chicago (60645)**  
Bell Industries  
3422 W. Touhy Ave.  
(312)982-9210  
Twx: 910-223-4519

**ILLINOIS, Elk Grove Village (60007)**  
Pioneer/Chicago  
1551 Carmen Drive  
(312)437-9680  
Twx: 910-222-1834

**ILLINOIS, Schiller Park (60176)**  
Hamilton/Avnet  
3901 N. 25th Ave.  
(312)678-6310  
Twx: 910-227-0060

**INDIANA, Carmel (46032)**  
Hamilton/Avnet  
485 Gradle Drive  
(317)844-9333  
Twx: 810-260-3966

**INDIANA, Indianapolis (46250)**  
Pioneer/Indiana  
6408 Castleplace Drive  
(317)849-7300  
Twx: 810-260-1794

**KANSAS, Merriam (66202)**  
Components Plus  
8015 W. 63rd St., Ste. 1  
(913)236-8555

**KANSAS, Overland Park (66215)**  
Hamilton/Avnet  
9219 Quivira Rd.  
(913)888-8900  
Twx: 910-743-0005

**MARYLAND, Baltimore (21227)**  
Components Plus  
4805 Benson Ave.  
(301)247-3620(MD)  
(202)621-2590(DC & N. VA)  
(800)638-8878(S. VA)

**MARYLAND, Columbia (21045)**  
Hamilton/Avnet  
6622 Oak Hall Lane  
(301)995-3500(MD)  
(301)621-5410(DC)  
Twx: 710-862-1861

**MARYLAND, Gaithersburg (20760)**  
Pioneer/Washington  
9100 Gaither Rd.  
(301)948-0710  
Twx: 710-828-0545

**MARYLAND, Gaithersburg (20760)**  
Marshall Industries  
16760 Oakmont Ave.  
(301)840-9450  
(301)710-828-0223

**MASSACHUSETTS, Burlington (01803)**  
Milgray Electronics  
79 Terrace Hall Ave.  
(617)272-6800  
Twx: 510-225-3673

**MASSACHUSETTS, Burlington (01803)**  
Marshall Industries  
1 Wilshire Rd.  
(617)272-8200  
Twx: 710-332-6359

**MASSACHUSETTS, Framingham (01701)**  
Cadence  
14 Burr St.  
(617)879-3000  
Twx: 710-380-6908

**MASSACHUSETTS, Framingham (01701)**  
Components Plus  
14 Burr St.  
(617)237-2503

**MASSACHUSETTS, Woburn (01801)**  
Hamilton/Avnet  
50 Tower Office Park  
(617)953-9700  
Twx: 710-393-0382

**MICHIGAN, Grand Rapids (49508)**  
Hamilton/Avnet  
2215-29th St. S.E.  
Space #85  
(616)243-8805

**MICHIGAN, Livonia (48150)**  
Hamilton/Avnet  
32487 Schoolcraft  
(313)522-4700  
Twx: 810-242-8775

**MICHIGAN, Livonia (48150)**  
Pioneer/Michigan  
13485 Stamford  
(313)525-1800  
Twx: 810-242-3271

**MINNESOTA, Minneapolis (55435)**  
Industrial Components  
5229 Edina Industrial Blvd.  
(612)831-2666  
Twx: 910-576-3153

**MINNESOTA, Minnetonka (55343)**  
Hamilton/Avnet  
10300 Bren Rd. East  
(612)932-0600  
Twx: 910-576-2729

**MINNESOTA, Minnetonka (55343)**  
Pioneer/Twin Cities  
10203 Bren Rd. East  
(612)935-5444

**MISSOURI, Earth City (63045)**  
Hamilton/Avnet  
13743 Shoreline Ct.  
(314)344-1200  
Twx: 910-762-0606

**NEW JERSEY, Cherry Hill (08003)**  
Hamilton/Avnet  
One Keystone Ave.  
(609)424-0100  
Twx: 710-940-0262

**NEW JERSEY, Clifton (07015)**  
Marshall Industries  
1111 Paulison Ave.  
(201)340-1900  
Twx: 910-989-7052

**NEW JERSEY, Fairfield (07006)**  
Hamilton/Avnet  
10 Industrial Rd.  
(201)575-3390  
Twx: 710-734-4388

**NEW JERSEY, Mt. Laurel (08057)**  
Marshall Industries  
102 Gaither Dr., Unit 2  
(609)234-9100 NJ (215)627-1920 PA  
Twx: 710-941-1361

**NEW MEXICO, Albuquerque (87123)**  
Alliance Electronics  
11030 Cochiti S.E.  
(505)293-3360  
Twx: 910-989-1151

**NEW MEXICO, Albuquerque (87123)**  
Bell Industries  
11728 Linn NE  
(505)292-2700  
Twx: 910-989-0625

**NEW MEXICO, Albuquerque (87119)**  
Hamilton/Avnet  
2524 Baylor Dr., SE  
(505)765-1500  
Twx: 910-989-0614

**NEW YORK, Buffalo (14202)**  
Summit Distributors, Inc.  
916 Main Street  
(716)887-2800  
Twx: 710-522-1692



# U.S. Distributors (Continued)

## NEW YORK, East Syracuse (13057)

Hamilton/Avnet  
1600 Corporate Circle  
(315)437-2642  
Twx: 710-541-1560

## NEW YORK, Endwell (13760)

Marshall Industries  
10 Hooper Rd.  
(607)754-1570  
Twx: 510-252-0194

## NEW YORK, Freeport (11520)

Milgray Electronics, Inc.  
191 Hanse Ave.  
(510)225-3673  
Twx: 516-546-5600

## NEW YORK, Hauppauge (11787)

Cadence  
40-4 Oser Ave.  
(516)231-6722

## NEW YORK, Hauppauge (11787)

Components Plus  
40 Oser Ave.  
(516)231-9200  
Twx: 510-227-9869

## NEW YORK, Hauppauge (11787)

Hamilton/Avnet  
5 Hub Drive  
(516)454-6000  
Twx: 510-224-6166

## NEW YORK, Port Chester (10573)

Zeus Components, Inc.  
100 Midland Ave.  
(914)937-7400  
Twx: 710-567-1248

## NEW YORK, Rochester (14623)

Hamilton/Avnet  
333 Metro Park  
(716)475-9130  
Twx: 510-253-5470

## NEW YORK, Rochester (14623)

Marshall Industries  
1260 Scottsville Rd.  
(716)235-7620  
Twx: 510-253-5470

## NORTH CAROLINA, Greensboro (27406)

Pioneer/NC  
103 Industrial Ave.  
(919)273-4441  
Twx: 510-925-1114

## NORTH CAROLINA, Raleigh (27609)

Hamilton/Avnet  
2803 Industrial Dr.  
(919)829-8030  
Twx: 510-928-1836

## OHIO, Cleveland (44105)

Pioneer/Cleveland  
4800 E. 131st Street  
(216)587-3600  
Twx: 810-422-2210

## OHIO, Dayton (45459)

Hamilton/Avnet  
954 Senate Dr.  
(513)433-0610  
Twx: 810-450-2531

## OHIO, Dayton (45424)

Pioneer/Dayton  
4433 Interpoint Blvd.  
(513)236-9900  
Twx: 810-459-1622

## OHIO, Warrensville Heights (44128)

Hamilton/Avnet  
4588 Emery Industrial Parkway  
(216)831-3500  
Twx: 810-427-9452

## OKLAHOMA, Tulsa (74129)

Quality Components  
9934 E. 21st St. South  
(918)664-8812

## OREGON, Lake Oswego (97034)

Hamilton/Avnet  
6024 SW Jean Road, Bldg. C, Ste. 10  
(503)635-8836  
Twx: 910-455-8179

## PENNSYLVANIA, Horsham (19044)

Pioneer Elec.  
261 Gibraltar Rd.  
(215)674-4000  
Twx: 510-665-6778

## PENNSYLVANIA, Pittsburgh (15238)

Pioneer/Pittsburgh  
259 Kappa Dr.  
(412)782-2300  
Twx: 710-795-3122

## TEXAS, Addison (75001)

Quality Components  
4257 Kellway Circle  
(214)387-4949  
Twx: 910-860-5459

## TEXAS, Austin (78758)

Hamilton/Avnet  
2401 Rutland Dr.  
(512)837-8911  
Twx: 910-874-1319

## TEXAS, Austin (78758)

Quality Components  
2427 Rutland Drive  
(512)835-0220  
Twx: 910-874-1377

## TEXAS, Dallas (75243)

Components Plus  
13777 No. Central Expwy., Suite 502  
(214)783-6060  
Twx: 910-867-9414

## TEXAS, Houston (77063)

Hamilton/Avnet  
8750 Westpark  
(713)780-1771  
Twx: 910-881-5523

## TEXAS, Houston (77036)

Quality Components  
6126 Westline  
(713)772-7100

## TEXAS, Irving (75062)

Hamilton/Avnet  
2111 W. Walnut Hill Lane  
(214)659-4151  
Twx: 910-860-5929

## UTAH, Salt Lake City (84120)

Bell Industries  
3639 West 2150 South  
(801)972-6969  
Twx: 910-925-5686

## UTAH, Salt Lake City (84119)

1585 West 2100 South  
(801)972-2800  
Twx: 910-925-4018

## WASHINGTON, Bellevue (98005)

Hamilton/Avnet  
14212 NE 21st St.  
(206)453-5844  
Twx: 910-443-2469

## WASHINGTON, Bellevue (98005)

Wyle Distribution Group  
1750 - 132nd Ave. NE  
(206)453-8300  
Twx: 910-443-2526

## WISCONSIN, Milwaukee (53214)

Marsh Electronics, Inc.  
1563 So. 101st St.  
(414)475-6000  
Twx: 910-262-3321

## WISCONSIN, New Berlin (53151)

Hamilton/Avnet  
2975 Moorland Rd.  
(414)784-4510  
Twx: 910-262-1182

# European Distributors/Representatives

## AUSTRIA

Ing. Ernst Steiner  
Hummelgasse 14  
A-1130 Vienna  
Tel: 0222/827474  
Tlx: 135026

## BELGIUM

Ritro Electronics BV  
172 Plantin en Moretuslei  
B-2000 Antwerpen-B  
Tel: 031-353272  
Tlx: 33637

## CYPRUS

Eltrom/Poly Electronics  
P.O. Box 5393  
Nicosia  
Tel: 21 61088  
Tlx: Tronics Cy 3529

## DENMARK

Ditz Schweitzer A.S.  
Vallensbaekvel 41  
Dk-2600 Glostrup  
Tel: (01)45-30-44  
Tlx: 33257

## FINLAND

Oy Findip AB  
Teollisuustie 7, P.O.B. 34  
SF 07200 Kauniainen  
Tel: 358-0-5052255  
Tlx: 12-3129

## FRANCE

Almex  
48 Rue de L'Aubepine  
92164 Antony Cedex  
Tel: 377-07-87  
Tlx: 250067

## Alrodis

40 Rue Villon  
69008 Lyon  
Tel: (78)00.87.12  
Tlx: 380636

Aquitaine Composants  
Avenue Gustave Eiffel  
B.P. 81  
33605 Pessac Cedex

Tel: (56)36.40.40  
Tlx: 550696F

Aquitaine Composants  
55 Avenue Louis Breguet  
31400 Toulouse  
Tel: (61)20.82.38

Aquitaine Composants  
183 Route de Paris  
86000 Poitiers  
Tel: (49) 88.60.50  
Tlx: 791525F

A. Baltzinger  
18-26 Route du Gal de Gaulle  
B.P. 63  
67042 Strausbourg Cedex  
Tel: (88)331852  
Tlx: 870952F

Quest Components  
57 Rue Mannoir de Servigne  
Z1, Route de Lorient  
B.P. 3209  
35013 Rennes Cedex  
Tel: (99)54.01.53  
Tlx: 740311

Sanelec Electronique  
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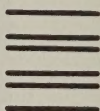
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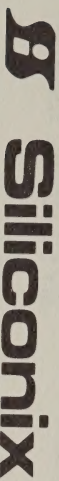


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